

Radiation Report

TPS7H6003-SP Neutron Displacement Damage (NDD)



ABSTRACT

This report presents the effect of neutron displacement damage (NDD) on the TPS7H6003-SP device. The TPS7H6003-SP showed a strong degree of hardness to neutron irradiation up to fluence level 1×10^{13} n/cm² .

The neutron irradiation test is a destructive test. Test procedure follows MIL-STD-883 method 1017 as guidance. The purpose of this test is to determine the device susceptibility to non-ionizing energy loss (NIEL) degradation. Objectives of the test are, to detect and measure the degradation of critical device parameters as a function of neutron fluence and to determine if these parameters are within specified limits after exposure to a specified level of neutron fluence.

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1 Device Information

1.1 Product Description

The TPS7H6003-SP is a 200-V radiation-hardness-assured, high voltage gate driver for GaN FETs for space applications. The TPS7H6003-SP is designed for high frequency, high efficiency applications. The driver features adjustable dead time capability, small 30-ns propagation delay and 5.5-ns high-side and low-side matching. This part also includes internal high-side and low-side LDOs that make sure that a drive voltage of 5-V regardless of supply voltage. The TPS7H6003-SP is packaged in a ceramic 48-HBX (CFP) package.

1.2 Device Details

Table 1-1 lists the device information and test conditions used in the NDD characterization.

Table 1-1. Device and Exposure Details

NDD Exposure Details	
TI Device	TPS7H6003-SP
TI Part Name	5962R2220101VXC
Device Function	Half Bridge Gate Driver
Package	48-pin CFP (HBX)
Technology	LBC7
Lot Number and Date Code	3008205 / 2324A
Sample Quantity	9 + 1 control unit
Exposure Facility	Fast Neutron Irradiation (FNI) Facility of University of Massachusetts Lowell Research Reactor (UMLRR)
Neutron Fluence (1-MeV equivalent) Level	1×10^{12} , 5×10^{12} , 1×10^{13} n/cm ²
Irradiation Temperature	25°C

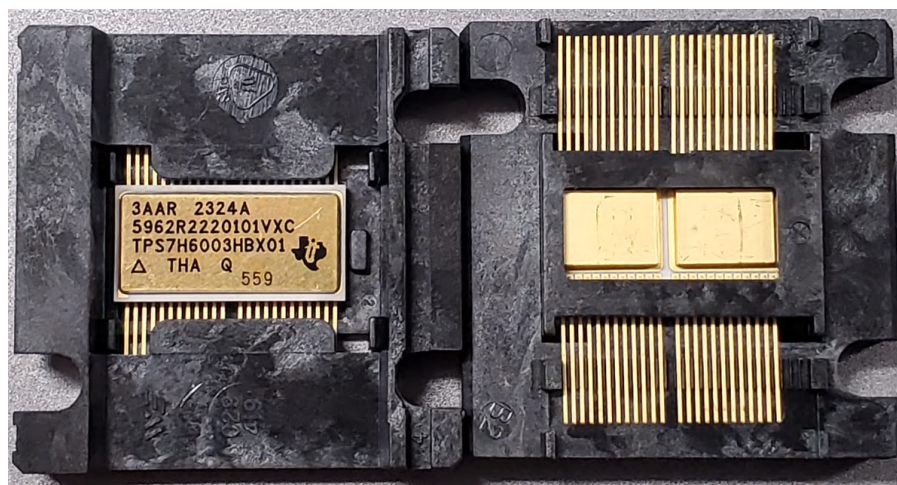


Figure 1-1. TPS7H6003-SP Device Used in Exposure

2 Neutron Displacement Test Setup

2.1 Test Overview

General test procedures adhere to MIL-STD-883, Method 1017 as a guide for neutron irradiation. The TPS7H6003-SP was electrically tested using the production automated test equipment (ATE) program at an ambient room temperature of 25°C before and after neutron irradiation.

2.2 Test Facility

The test facility was the Fast Neutron Irradiation (FNI) Facility of University of Massachusetts Lowell Research Reactor. The neutron fluence for this irradiation was measured using ASTM E-265 *Measuring Reaction Rates and Fast Neutron Fluence by Radioactivation of Sulfur-32* and correlated to the measured reactor power level. All irradiation conditions required under ASTM 722 were met. This includes neutron fluence, distribution and uncertainty. The Average Integrated Neutron Fluence, 1-MeV(Si) equivalent, reflects these factors.

Detailed information of the radiation facility is available [here](#).

2.3 Test Setup Details

Devices were irradiated at three fluence levels in unbiased conditions: 1×10^{12} n / cm², 5×10^{12} n / cm² and 1×10^{13} n / cm².

Table 2-1. Neutron Irradiation Conditions

Group	Sample Quantity	Neutron Fluence (n / cm ²)	Bias
A	3	1.0×10^{12}	Unbiased
B	3	5.0×10^{12}	Unbiased
C	3	1.0×10^{13}	Unbiased
Control Unit	1	N/A	N/A

3 Test Results

3.1 NDD Characterization Summary

The results show that all devices were fully functional and within specification limits. A sample size of nine units was exposed for neutron irradiation and an additional unirradiated control unit was used as correlation.

Overall, the TPS7H6003-SP showed a strong degree of hardness to neutron irradiation up to fluence level $1 \times 10^{13} \text{ n/cm}^2$. The measurements taken post-irradiation for each sample set showed a marginal shift for most parameters at each fluence level. The parameters that showed a greater degree of change between pre- and post- irradiation were still within the electrical performance characteristics specified in the [Table 3-1](#).

Electrical testing is done for pre- and post- neutron irradiation by ATE electrical test is done at an ambient room temperature of 25°C. Parameters not listed in [Table 3-1](#) are omitted either because there is no parametric data or because verification was done through bench testing.

See [Appendix A](#) for NDD test results.

3.2 Data Sheet Electrical Parameters and Associated Tests

Table 3-1. TPS7H6003-SP Data Sheet Electrical Parameters

Parameter		Test Conditions		MIN	MAX	UNIT	Test Number
SUPPLY CURRENTS							
I _{QLS}	Low-side quiescent current	VIN = 12 V, BOOT = 10 V	MODE = PWM, EN = 0 V	6.8	mA	35, 36, 37	
			MODE = IIM, LI = HI = 0 V	8		35.2, 36.2, 37.2	
I _{QHS}	High-side quiescent current	VIN = 12 V, BOOT = 10 V	MODE = PWM, EN = 0 V	6.3	mA	35.1, 36.1, 37.1	
			MODE = IIM, LI = HI = 0 V	6.3		35.3, 36.3, 37.3	
I _{OP_LS}	Low-side operating current	MODE = PWM, no load for HOL and HOH	f = 500 kHz	9	mA	35.6, 36.6, 37.6	
			f = 1 MHz	11		35.8, 36.8, 37.8	
			f = 2 MHz	16		35.10, 36.10, 37.10	
			f = 5 MHz	30		35.12, 36.12, 37.12	
		MODE = IIM, no load for HOL and HOH	f = 500 kHz	9		35.14, 36.14, 37.14	
			f = 1 MHz	12		35.16, 36.16, 37.16	
			f = 2 MHz	17		35.18, 36.18, 37.18	
			f = 5 MHz	30		35.20, 36.20, 37.20	
I _{OP_HS}	High-side operating current	MODE = PWM, no load for HOL and HOH	f = 500 kHz	6.5	mA	35.7, 36.7, 37.7	
			f = 1 MHz	8		35.9, 36.9, 37.9	
			f = 2 MHz	10.5		35.11, 36.11, 37.11	
			f = 5 MHz	17.5		35.13, 36.13, 37.13	
		MODE = IIM, no load for HOL and HOH	f = 500 kHz	6.5		35.15, 36.15, 37.15	
			f = 1 MHz	8		35.17, 36.17, 37.17	
			f = 2 MHz	10.5		35.19, 36.19, 37.19	
			f = 5 MHz	15		35.21, 36.21, 37.21	
GATE DRIVER							
V _{OL}	Low-level output voltage	I _{OL} = 100 mA	0.15	V	45, 46, 47		
BP5x – V _{OH}	High-level output voltage	I _{OH} = 100 mA	0.3	V	45.2, 46.2, 47.2		
I _{OH}	Peak source current	HOH, LOH = 0 V, BP5x = 5 V	0.7	2.3	A	50, 50.1, 51, 51.1, 52, 52.1	
I _{OL}	Peak sink current	HOL, LOL = 5 V, BP5x = 5 V	1.6	4.6	A	50.2, 51.2, 52.2	
INTERNAL REGULATORS							
V _{BP5L}	Low-side 5-V regulator output voltage	C _{BP5L} = 1 μF	4.75	5.175	V	60.1, 60.4, 60.7, 60.10, 60.13, 60.16, 60.19, 60.22, 61.1, 61.4, 61.7, 61.10, 61.13, 61.16, 61.19, 61.22, 62.1, 62.4, 62.7, 62.10, 62.13, 62.16, 62.19, 62.22	
V _{BP5H}	High-side 5-V regulator output voltage	C _{BP5H} = 1 μF	4.75	5.175	V	60.2, 60.5, 60.8, 60.11, 60.14, 60.17, 60.20, 60.23, 61.2, 61.5, 61.8, 61.11, 61.14, 61.17, 61.2, 61.23, 62.2, 62.5, 62.8, 62.11, 62.14, 62.17, 62.20, 62.23	
V _{BP7L}	7-V regulator output voltage	C _{BP7L} = 1 μF	6.65	7.35	V	60, 60.3, 60.6, 60.9, 60.12, 60.15, 60.18, 60.21, 61.0, 61.3, 61.6, 61.9, 61.12, 61.15, 61.18, 61.21, 61.23, 62, 62.3, 62.6, 62.9, 62.12, 62.15, 62.18, 62.21	
UNDERVOLTAGE PROTECTION							
BP5H _R	BP5H UVLO rising threshold	C _{BP5H} = 1 μF	4	4.5	V	85.1, 86.1, 87.1	
BP5H _F	BP5H UVLO falling threshold	C _{BP5H} = 1 μF	3.8	4.3	V	85.2, 86.2, 87.2	
BP5L _R	BP5L UVLO rising threshold	C _{BP5L} = 1 μF	4	4.5	V	80.1, 81.1, 82.1	
BP5L _F	BP5L UVLO falling threshold	C _{BP5L} = 1 μF	3.8	4.3	V	80.2, 81.2, 82.2	
BP7L _R	BP7L UVLO rising threshold	C _{BP7L} = 1 μF	6.2	6.8	V	80.4, 81.4, 82.4	
BP7L _F	BP7L UVLO falling threshold	C _{BP7L} = 1 μF	5.9	6.5	V	80.5, 81.5, 82.5	
VIN _R	VIN UVLO rising threshold		8	9	V	70	

Table 3-1. TPS7H6003-SP Data Sheet Electrical Parameters (continued)

Parameter		Test Conditions	MIN	MAX	UNIT	Test Number	
VIN _F	VIN UVLO falling threshold		7.5	8.5	V	70.1	
BOOT _R	BOOT UVLO rising threshold		6.6	7.4	V	75.0	
BOOT _F	BOOT UVLO falling threshold		6.2	7	V	75.1	
INPUT PINS							
V _{IR}	Input rising edge threshold		1.8	2.65	V	90, 91.0, 92, 90.3, 91.3, 92.3	
V _{IF}	Input falling edge threshold		1.15	1.85	V	90.1, 91.1, 92.1, 90.4, 91.4, 92.4	
R _{PD}	Input pull-down resistance	V = 2.15 V applied at input (EN_HI or PWM_LI)	100	400	kΩ	90.6, 90.7, 91.6, 91.7, 92.6, 92.7	
PROGRAMMABLE DEAD TIME							
T _{DLH}	LO off to HO on dead time	MODE = PWM, LO falling to HO rising (90% to 10%), f ≤ 2 MHz	RLH = 3.32 kΩ	0	10	ns	95, 95.5, 95.10, 96, 96.5, 96.10, 97, 97.5, 97.10
			RLH = 11.8 kΩ	8.0	15.5		95.1, 95.6, 95.11, 96.1, 96.6, 96.11, 97.1, 97.6, 97.11
			RLH = 21 kΩ	15.5	24		95.2, 95.7, 95.12, 96.2, 96.7, 96.12, 97.2, 97.7, 97.12
			RLH = 52.3 kΩ	36	59		95.3, 95.8, 95.13, 96.3, 96.8, 96.13, 97.3, 97.8, 97.13
			RLH = 105 kΩ	74	113.5		95.4, 95.9, 95.14, 96.4, 96.9, 96.14, 97.4, 97.9, 97.14
T _{DHL}	HO off to LO on dead time	MODE = PWM, HO falling to LO rising (90% to 10%), f ≤ 2 MHz	RHL = 7.87 kΩ	0	10	ns	95.19, 95.24, 95.29, 96.19, 96.24, 96.29, 97.19, 97.24, 97.29
			RHL = 13.3 kΩ	6	15		95.2, 95.25, 95.3, 96.20, 96.25, 96.30, 97.2, 97.25, 97.3
			RHL = 23.7 kΩ	16	24.5		95.21, 95.26, 95.31, 96.21, 96.26, 96.31, 97.21, 97.26, 97.31
			RHL = 57.6 kΩ	44	61		95.22, 95.27, 95.32, 96.22, 96.27, 96.32, 97.22, 97.27, 97.32
			RHL = 113 kΩ	86	125		95.23, 95.28, 95.33, 96.23, 96.28, 96.33, 97.23, 97.28, 97.33
BOOTSTRAP DIODE SWITCH							
	Bootstrap diode switch parallel resistance	I _{BST_SW} = 1 mA	0.8	1.2	kΩ	100.1, 101.1, 102.1	
POWER GOOD							
	Logic-Low output	I _{FLT} = 1 mA		0.4	V	105, 106, 107	
	PGOOD internal resistance	BP5L = 5 V, BP7L = 7 V, VIN = 12 V	0.7	1.9	MΩ	105.2, 106.2, 107.2	
	Minimum BP5L voltage for valid PGOOD output			2.45	V	105.1, 106.1, 107.1	

4 Applicable and Reference Documents

4.1 Applicable Documents

- Texas Instruments, [TPS7H6003-SP Radiation-Hardness-Assured 200-V, 1.3-A, 2.5-A, Half-Bridge GaN FET Gate Driver](#), data sheet.
- Texas Instruments, [TPS7H6003EVM-CVAL](#) , EVM user's guide.
- Texas Instruments, [TPS7H6003-SP Single-Event Effects \(SEE\) Report](#), radiation report.

4.2 Reference Documents

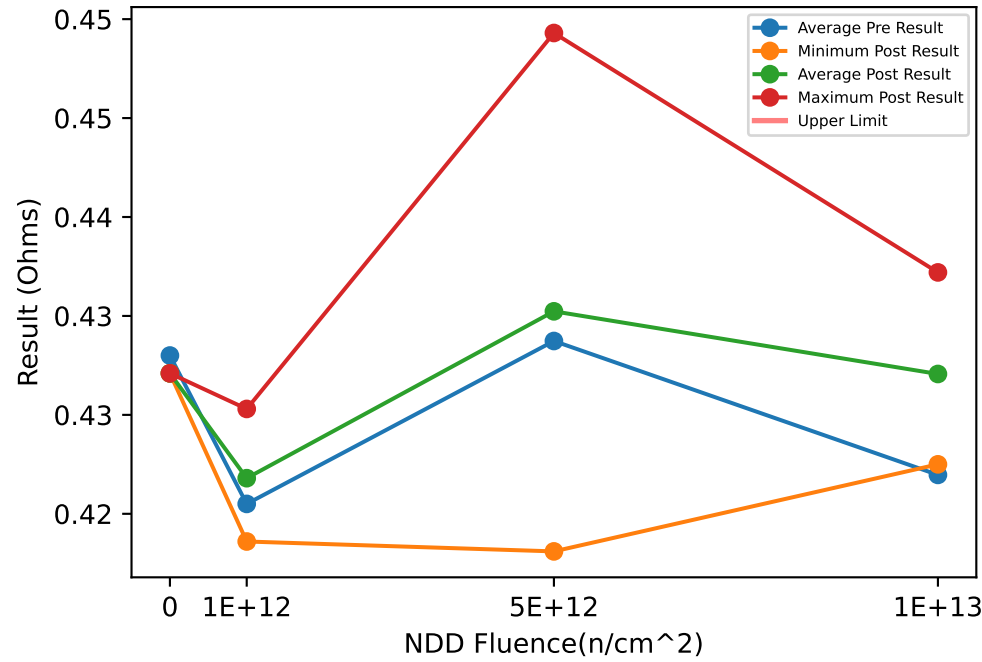
Texas Instruments neutron irradiation test follow the guideline from MIL-STD-883 TM 1017. The document is available in Defense Logistic Agency's website.

A Appendix: NDD Report Data

This appendix contains the detailed NDD test results.

Device Test: 100.0 R_BST_SW(Bootstrap Diode Switch Resistance VIN_10V)

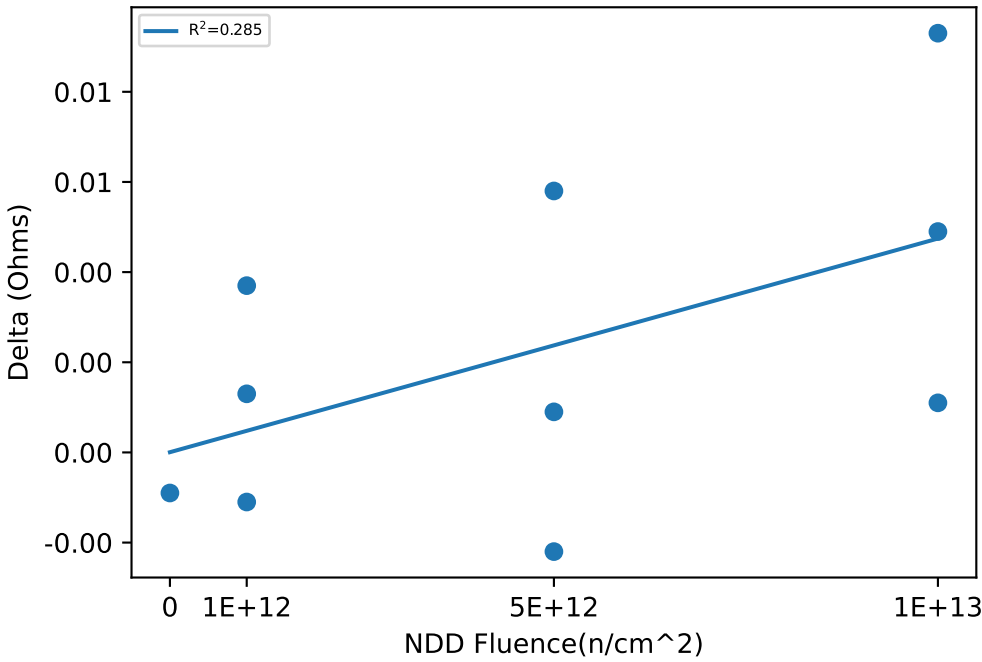
NDD vs Result Stats



Test Results (No Limits Specified (Ohms))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	0.4252	0.4265	0.0013
551	1e+12	NDD	0.4266	0.4303	0.0037
552	1e+12	NDD	0.4247	0.4236	-0.0011
553	5e+12	NDD	0.4275	0.4333	0.0058
554	5e+12	NDD	0.4484	0.4493	0.0009
555	5e+12	NDD	0.4253	0.4231	-0.0022
556	1e+13	NDD	0.4222	0.4315	0.0093
557	1e+13	NDD	0.4226	0.4275	0.0049
558	1e+13	NDD	0.4361	0.4372	0.0011
559	0	NDD, Ctrl	0.433	0.4321	-0.0009

NDD vs Post - Pre Exposure Delta

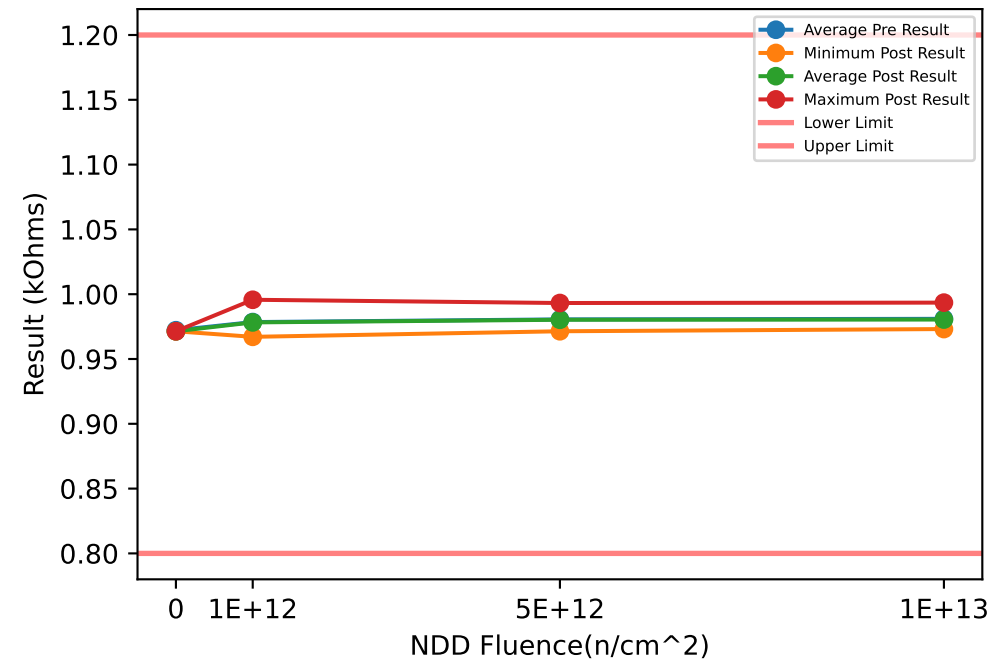


Test Statistics (Ohms)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.433	0.433	0.433		0.4321	0.4321	0.4321		-0.0009	-0.0009	-0.0009	
1e+12	0.4247	0.4255	0.4266	0.00098489	0.4236	0.4268	0.4303	0.0033601	-0.0011	0.0013	0.0037	0.0024
5e+12	0.4253	0.43373	0.4484	0.012749	0.4231	0.43523	0.4493	0.013207	-0.0022	0.0015	0.0058	0.0040336
1e+13	0.4222	0.42697	0.4361	0.0079122	0.4275	0.43207	0.4372	0.0048748	0.0011	0.0051	0.0093	0.0041037

Device Test: 100.1 R_BST_SW_PARALLEL(Bootstrap Diode Switch Parallel Resistance VIN_10V)

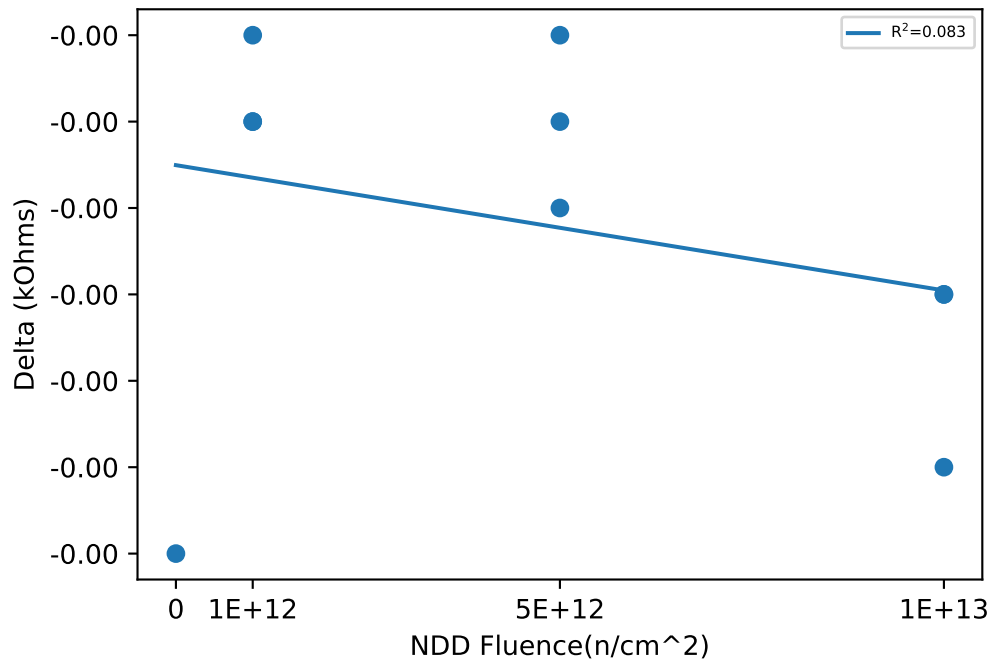
NDD vs Result Stats



Test Results (Lower Limit = 0.8, Upper Limit = 1.2 (kOhms))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	0.9722	0.9719	-0.0003
551	1e+12	NDD	0.996	0.9957	-0.0003
552	1e+12	NDD	0.9673	0.9671	-0.0002
553	5e+12	NDD	0.9718	0.9714	-0.0004
554	5e+12	NDD	0.9764	0.9762	-0.0002
555	5e+12	NDD	0.9935	0.9932	-0.0003
556	1e+13	NDD	0.994	0.9935	-0.0005
557	1e+13	NDD	0.9752	0.9747	-0.0005
558	1e+13	NDD	0.9738	0.9731	-0.0007
559	0	NDD, Ctrl	0.9722	0.9714	-0.0008

NDD vs Post - Pre Exposure Delta

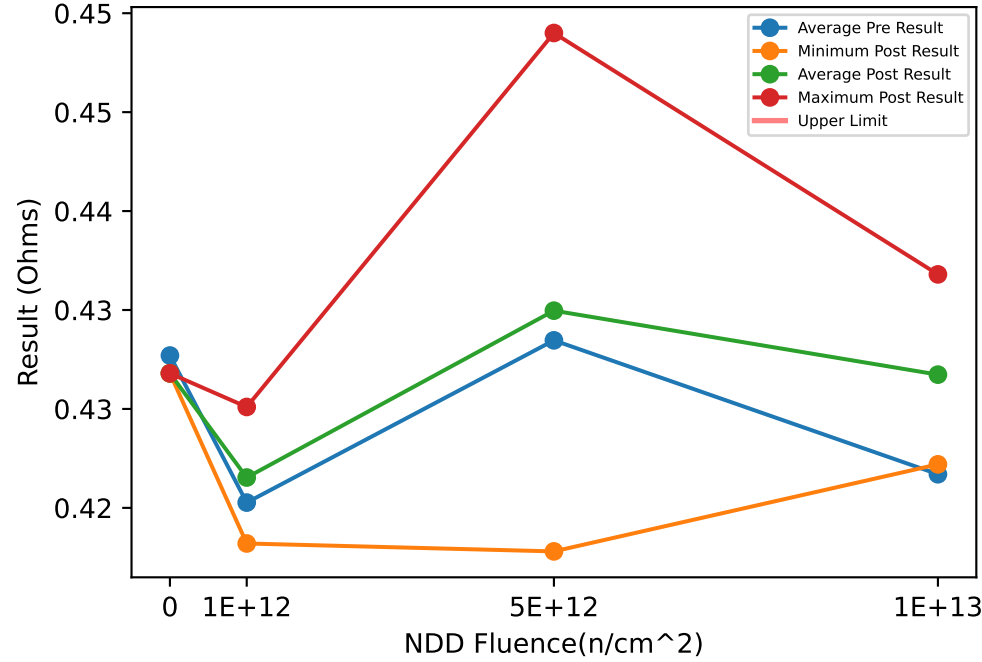


Test Statistics (kOhms)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9722	0.9722	0.9722		0.9714	0.9714	0.9714		-0.0008	-0.0008	-0.0008	
1e+12	0.9673	0.9785	0.996	0.015352	0.9671	0.97823	0.9957	0.015316	-0.0003	-0.00026667	-0.0002	5.7735e-05
5e+12	0.9718	0.98057	0.9935	0.011434	0.9714	0.98027	0.9932	0.011455	-0.0004	-0.0003	-0.0002	0.0001
1e+13	0.9738	0.981	0.994	0.01128	0.9731	0.98043	0.9935	0.011344	-0.0007	-0.00056667	-0.0005	0.00011547

Device Test: 101.0 R_BST_SW(Bootstrap Diode Switch Resistance VIN_12V)

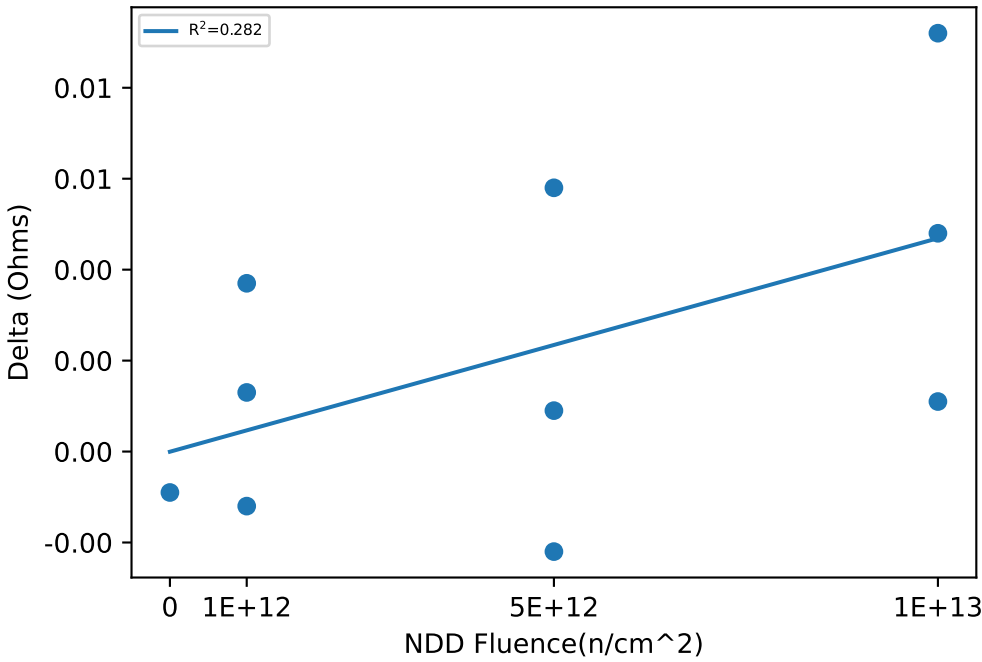
NDD vs Result Stats



Test Results (No Limits Specified (Ohms))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	0.425	0.4263	0.0013
551	1e+12	NDD	0.4264	0.4301	0.0037
552	1e+12	NDD	0.4244	0.4232	-0.0012
553	5e+12	NDD	0.4273	0.4331	0.0058
554	5e+12	NDD	0.4481	0.449	0.0009
555	5e+12	NDD	0.425	0.4228	-0.0022
556	1e+13	NDD	0.422	0.4312	0.0092
557	1e+13	NDD	0.4224	0.4272	0.0048
558	1e+13	NDD	0.4357	0.4368	0.0011
559	0	NDD, Ctrl	0.4327	0.4318	-0.0009

NDD vs Post - Pre Exposure Delta

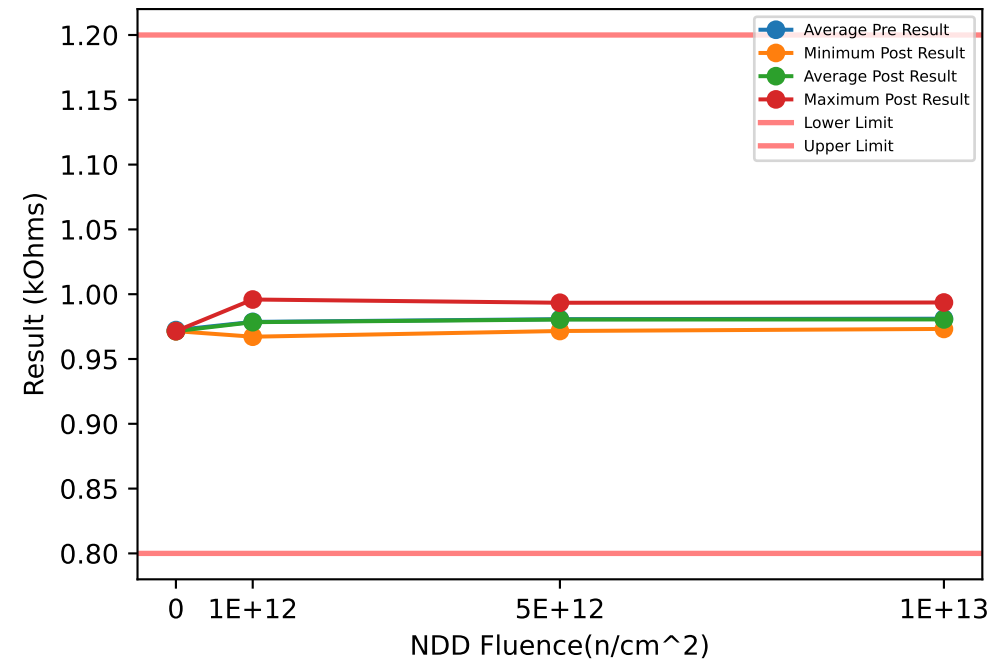


Test Statistics (Ohms)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.4327	0.4327	0.4327		0.4318	0.4318	0.4318		-0.0009	-0.0009	-0.0009	
1e+12	0.4244	0.42527	0.4264	0.0010263	0.4232	0.42653	0.4301	0.0034559	-0.0012	0.0012667	0.0037	0.0024502
5e+12	0.425	0.43347	0.4481	0.012725	0.4228	0.43497	0.449	0.013199	-0.0022	0.0015	0.0058	0.0040336
1e+13	0.422	0.4267	0.4357	0.0077968	0.4272	0.43173	0.4368	0.0048222	0.0011	0.0050333	0.0092	0.004055

Device Test: 101.1 R_BST_SW_PARALLEL(Bootstrap Diode Switch Parallel Resistance VIN_12V)

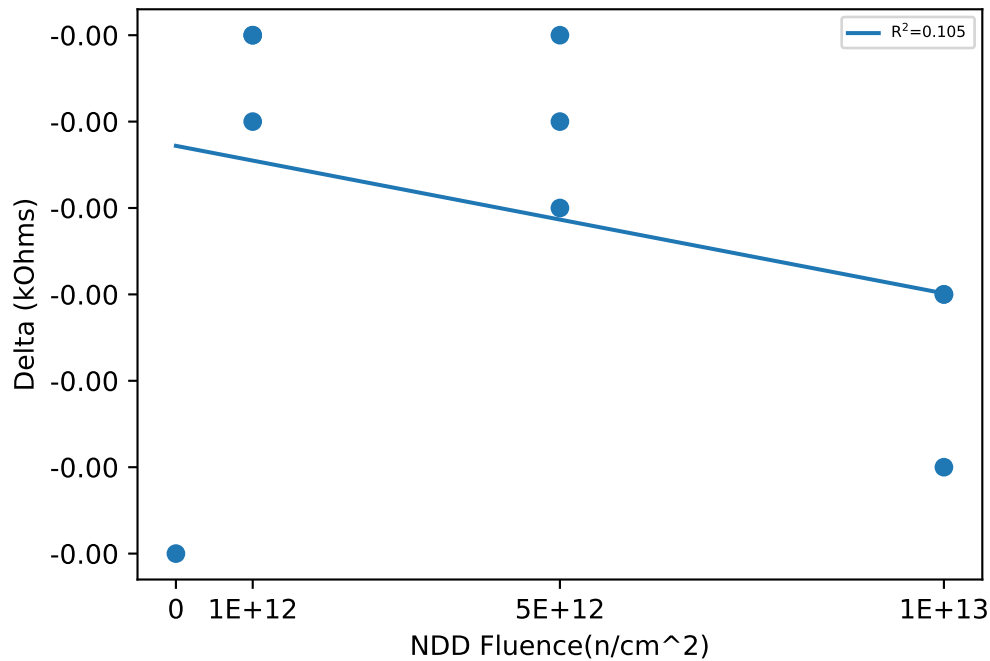
NDD vs Result Stats



Test Results (Lower Limit = 0.8, Upper Limit = 1.2 (kOhms))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	0.9723	0.9721	-0.0002
551	1e+12	NDD	0.9961	0.9959	-0.0002
552	1e+12	NDD	0.9675	0.9672	-0.0003
553	5e+12	NDD	0.972	0.9716	-0.0004
554	5e+12	NDD	0.9766	0.9763	-0.0003
555	5e+12	NDD	0.9936	0.9934	-0.0002
556	1e+13	NDD	0.9941	0.9936	-0.0005
557	1e+13	NDD	0.9753	0.9748	-0.0005
558	1e+13	NDD	0.9739	0.9732	-0.0007
559	0	NDD, Ctrl	0.9723	0.9715	-0.0008

NDD vs Post - Pre Exposure Delta

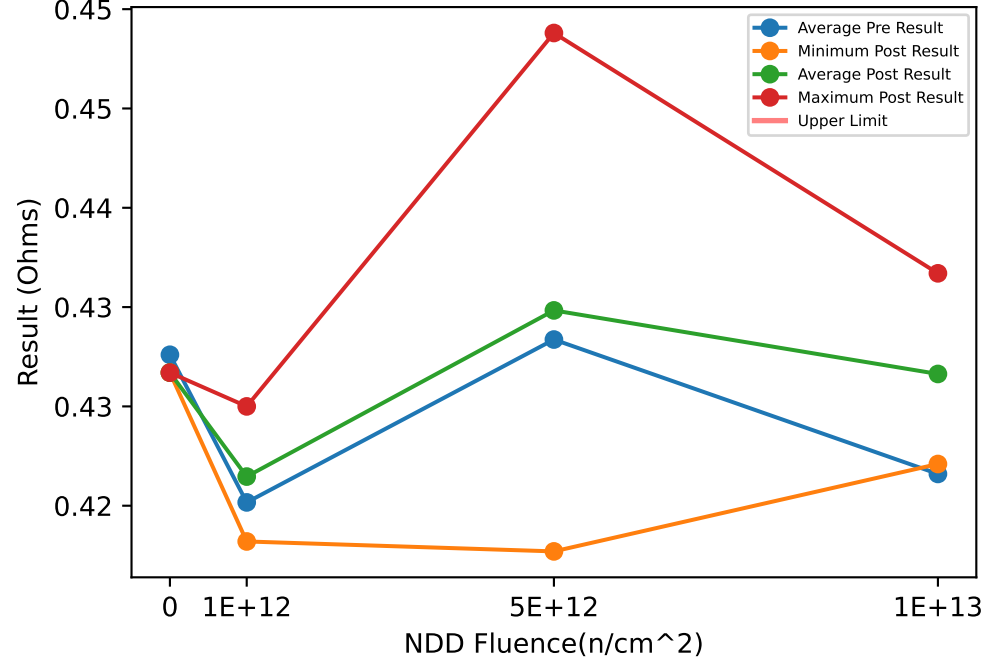


Test Statistics (kOhms)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9723	0.9723	0.9723		0.9715	0.9715	0.9715		-0.0008	-0.0008	-0.0008	
1e+12	0.9675	0.97863	0.9961	0.015316	0.9672	0.9784	0.9959	0.015352	-0.0003	-0.00023333	-0.0002	5.7735e-05
5e+12	0.972	0.98073	0.9936	0.011378	0.9716	0.98043	0.9934	0.011473	-0.0004	-0.0003	-0.0002	0.0001
1e+13	0.9739	0.9811	0.9941	0.01128	0.9732	0.98053	0.9936	0.011344	-0.0007	-0.00056667	-0.0005	0.00011547

Device Test: 102.0 R_BST_SW(Bootstrap Diode Switch Resistance VIN_14V)

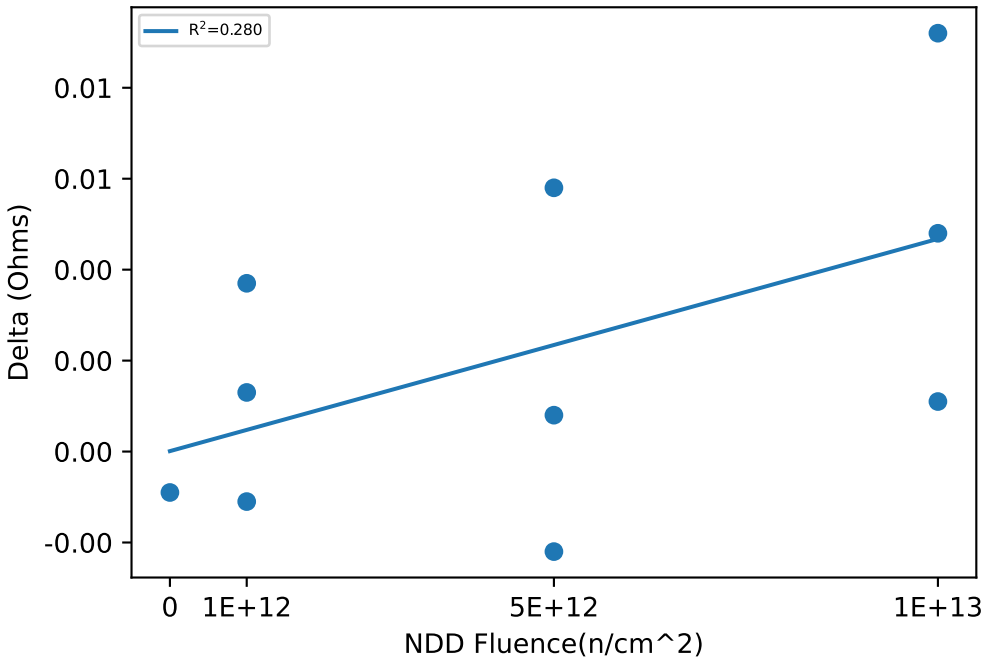
NDD vs Result Stats



Test Results (No Limits Specified (Ohms))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	0.4249	0.4262	0.0013
551	1e+12	NDD	0.4263	0.43	0.0037
552	1e+12	NDD	0.4243	0.4232	-0.0011
553	5e+12	NDD	0.4272	0.433	0.0058
554	5e+12	NDD	0.448	0.4488	0.0008
555	5e+12	NDD	0.4249	0.4227	-0.0022
556	1e+13	NDD	0.4219	0.4311	0.0092
557	1e+13	NDD	0.4223	0.4271	0.0048
558	1e+13	NDD	0.4356	0.4367	0.0011
559	0	NDD, Ctrl	0.4326	0.4317	-0.0009

NDD vs Post - Pre Exposure Delta

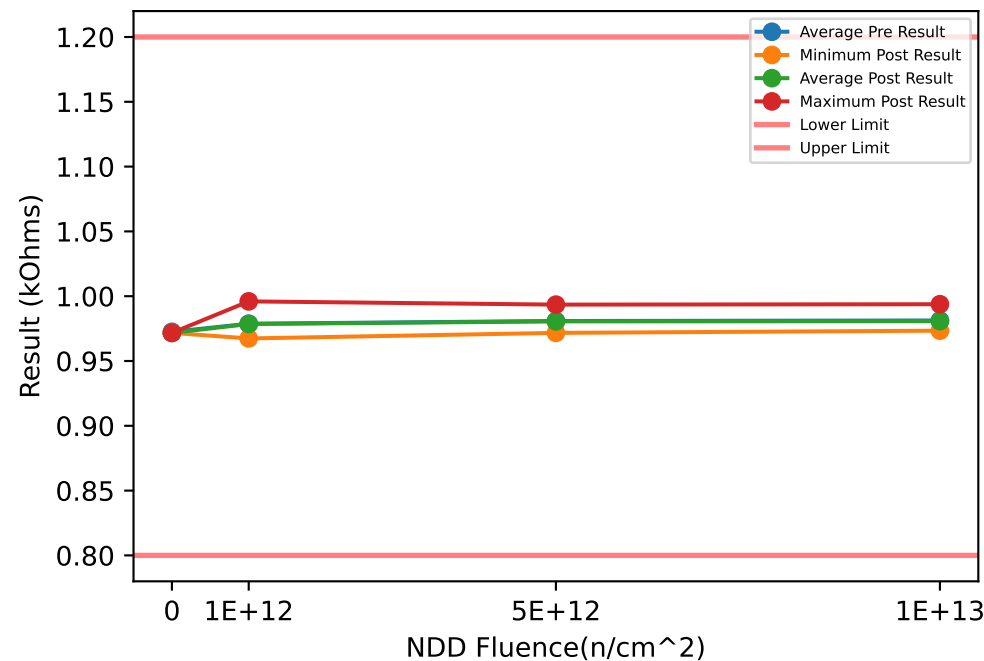


Test Statistics (Ohms)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.4326	0.4326	0.4326		0.4317	0.4317	0.4317		-0.0009	-0.0009	-0.0009	
1e+12	0.4243	0.42517	0.4263	0.0010263	0.4232	0.42647	0.43	0.0034078	-0.0011	0.0013	0.0037	0.0024
5e+12	0.4249	0.43337	0.448	0.012725	0.4227	0.43483	0.4488	0.013146	-0.0022	0.0014667	0.0058	0.0040415
1e+13	0.4219	0.4266	0.4356	0.0077968	0.4271	0.43163	0.4367	0.0048222	0.0011	0.0050333	0.0092	0.004055

Device Test: 102.1 R_BST_SW_PARALLEL(Bootstrap Diode Switch Parallel Resistance VIN_14V)

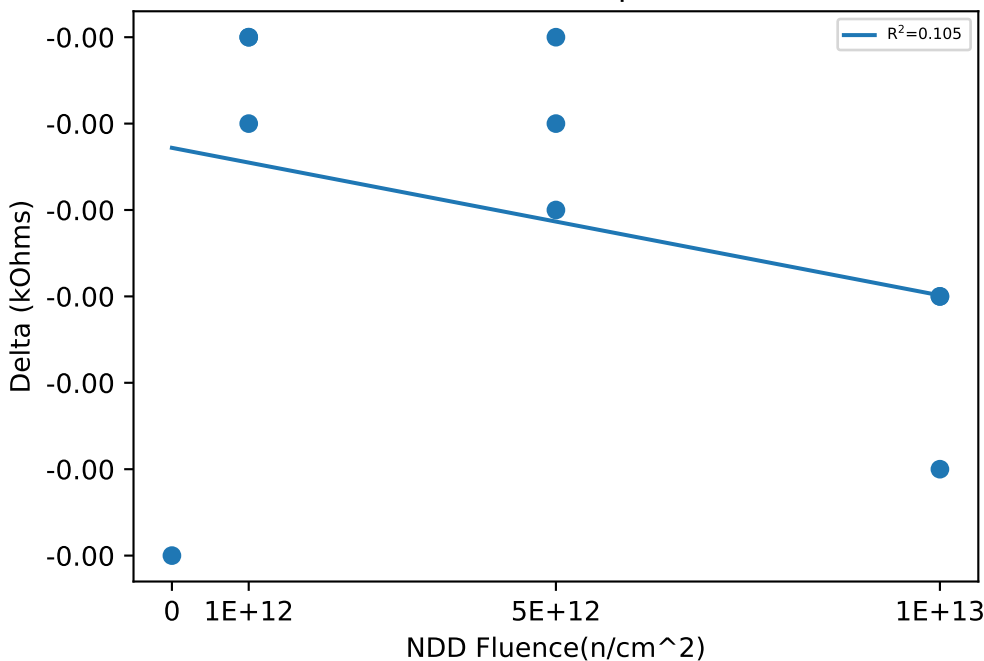
NDD vs Result Stats



Test Results (Lower Limit = 0.8, Upper Limit = 1.2 (kOhms))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	0.9725	0.9722	-0.0003
551	1e+12	NDD	0.9962	0.996	-0.0002
552	1e+12	NDD	0.9676	0.9674	-0.0002
553	5e+12	NDD	0.9721	0.9717	-0.0004
554	5e+12	NDD	0.9767	0.9765	-0.0002
555	5e+12	NDD	0.9938	0.9935	-0.0003
556	1e+13	NDD	0.9943	0.9938	-0.0005
557	1e+13	NDD	0.9754	0.9749	-0.0005
558	1e+13	NDD	0.9741	0.9734	-0.0007
559	0	NDD, Ctrl	0.9725	0.9717	-0.0008

NDD vs Post - Pre Exposure Delta

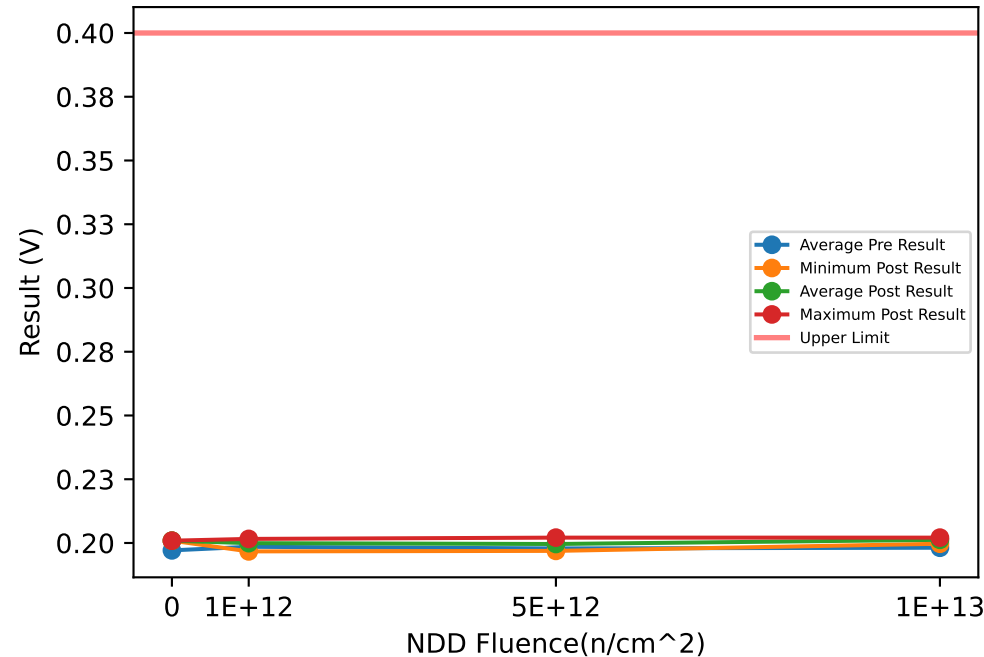


Test Statistics (kOhms)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9725	0.9725	0.9725		0.9717	0.9717	0.9717		-0.0008	-0.0008	-0.0008	
1e+12	0.9676	0.97877	0.9962	0.015295	0.9674	0.97853	0.996	0.015316	-0.0003	-0.00023333	-0.0002	5.7735e-05
5e+12	0.9721	0.98087	0.9938	0.011434	0.9717	0.98057	0.9935	0.011455	-0.0004	-0.0003	-0.0002	0.0001
1e+13	0.9741	0.98127	0.9943	0.011306	0.9734	0.9807	0.9938	0.01137	-0.0007	-0.00056667	-0.0005	0.00011547

Device Test: 105.0 V_PGOOD_OL(PGOOD Logic Low Outupt)

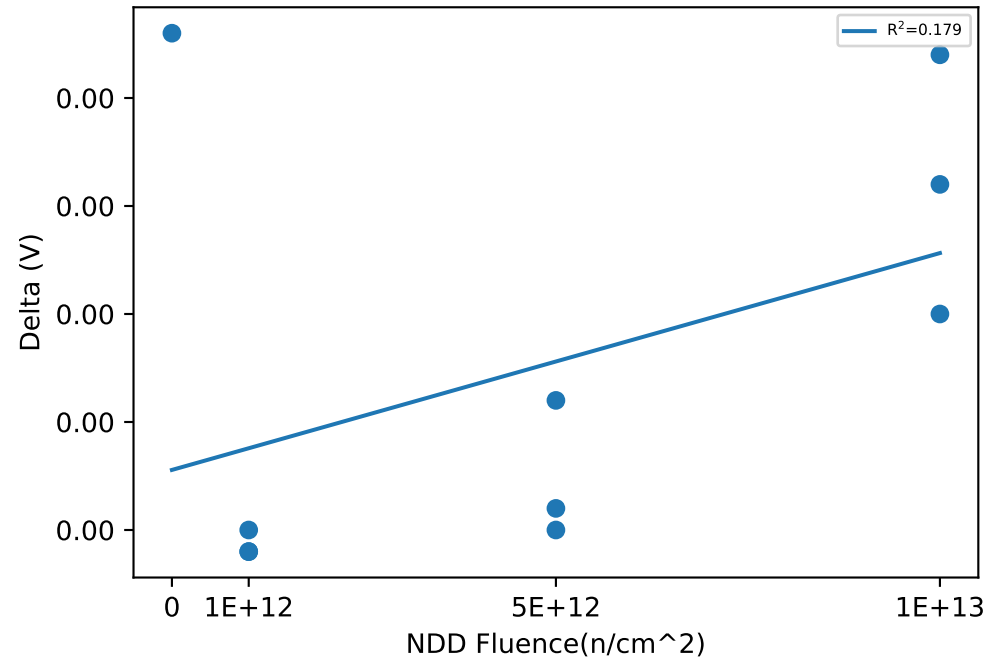
NDD vs Result Stats



Test Results (Upper Limit = 0.4 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	0.2001	0.2015	0.0014
551	1e+12	NDD	0.1953	0.1967	0.0014
552	1e+12	NDD	0.2001	0.2016	0.0015
553	5e+12	NDD	0.1977	0.1998	0.0021
554	5e+12	NDD	0.2005	0.2021	0.0016
555	5e+12	NDD	0.1954	0.1969	0.0015
556	1e+13	NDD	0.1994	0.2019	0.0025
557	1e+13	NDD	0.1966	0.1997	0.0031
558	1e+13	NDD	0.1984	0.2021	0.0037
559	0	NDD, Ctrl	0.1971	0.2009	0.0038

NDD vs Post - Pre Exposure Delta

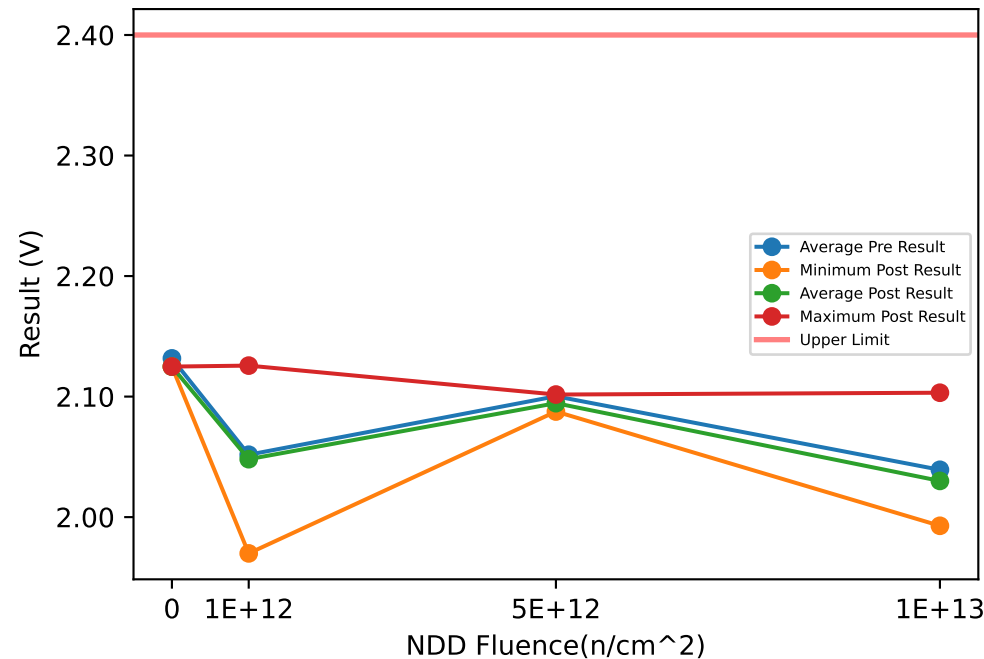


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1971	0.1971	0.1971		0.2009	0.2009	0.2009		0.0038	0.0038	0.0038	
1e+12	0.1953	0.1985	0.2001	0.0027713	0.1967	0.19993	0.2016	0.0028006	0.0014	0.0014333	0.0015	5.7735e-05
5e+12	0.1954	0.19787	0.2005	0.0025541	0.1969	0.1996	0.2021	0.0026058	0.0015	0.0017333	0.0021	0.00032146
1e+13	0.1966	0.19813	0.1994	0.0014189	0.1997	0.20123	0.2021	0.0013317	0.0025	0.0031	0.0037	0.0006

Device Test: 105.1 V_BP5L_MIN_FOR_PGOOD(Min BP5L for Valid PGOOD)

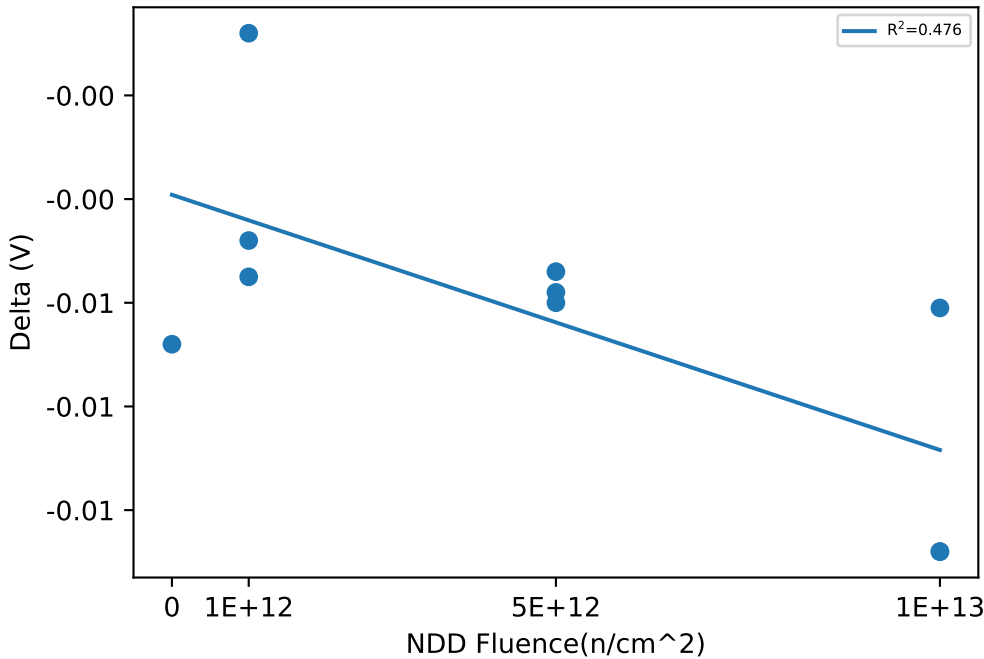
NDD vs Result Stats



Test Results (Upper Limit = 2.4 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	2.1265	2.1257	-0.0008
551	1e+12	NDD	1.9747	1.9699	-0.0048
552	1e+12	NDD	2.0541	2.0486	-0.0055
553	5e+12	NDD	2.0936	2.0876	-0.006
554	5e+12	NDD	2.1071	2.1017	-0.0054
555	5e+12	NDD	2.1001	2.0943	-0.0058
556	1e+13	NDD	2.0049	1.9941	-0.0108
557	1e+13	NDD	2.114	2.1032	-0.0108
558	1e+13	NDD	1.9989	1.9928	-0.0061
559	0	NDD, Ctrl	2.1317	2.1249	-0.0068

NDD vs Post - Pre Exposure Delta

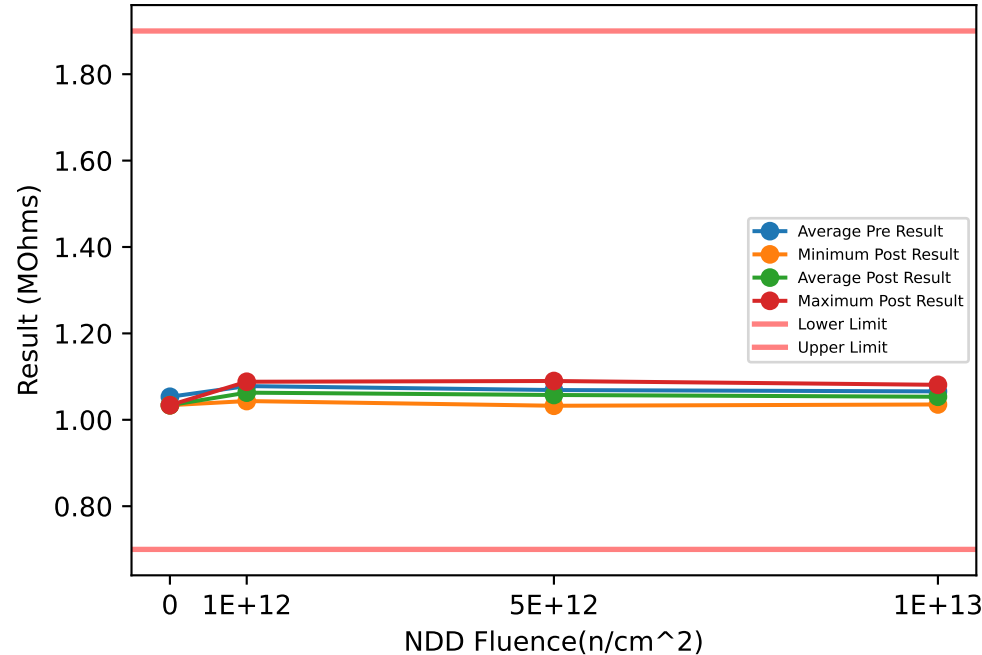


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.1317	2.1317	2.1317		2.1249	2.1249	2.1249		-0.0068	-0.0068	-0.0068	
1e+12	1.9747	2.0518	2.1265	0.075927	1.9699	2.0481	2.1257	0.077901	-0.0055	-0.0037	-0.0008	0.0025357
5e+12	2.0936	2.1003	2.1071	0.0067515	2.0876	2.0945	2.1017	0.0070529	-0.006	-0.0057333	-0.0054	0.00030551
1e+13	1.9989	2.0393	2.114	0.06479	1.9928	2.03	2.1032	0.063368	-0.0108	-0.0092333	-0.0061	0.0027135

Device Test: 105.2 I_PGOOD_PD_RES(PGOOD Internal Resistance VIN_10V)

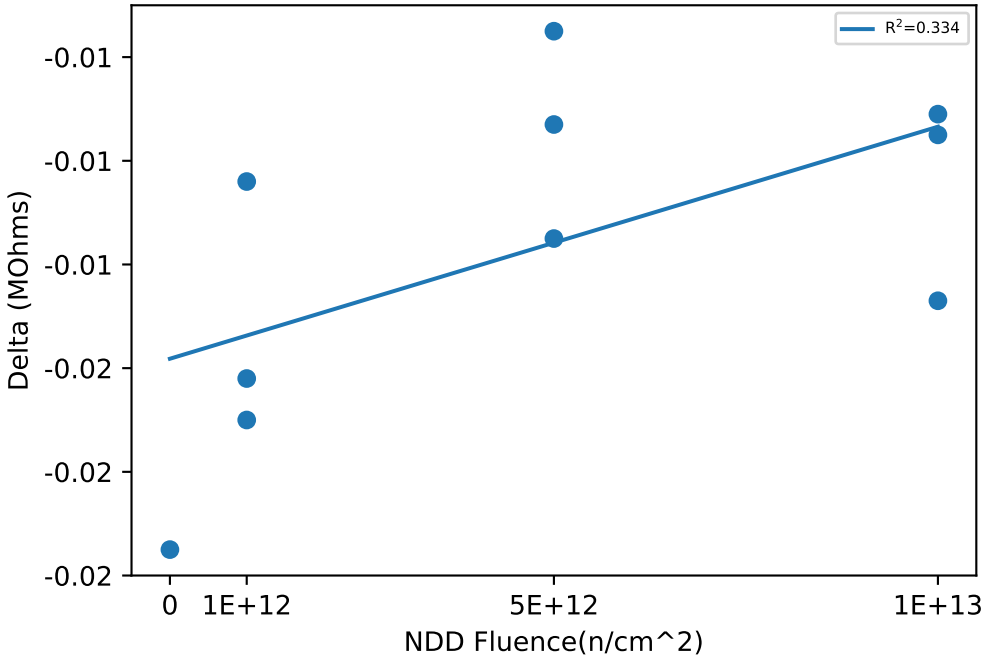
NDD vs Result Stats



Test Results (Lower Limit = 0.7, Upper Limit = 1.9 (MOhms))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	1.0604	1.0434	-0.017
551	1e+12	NDD	1.1043	1.0881	-0.0162
552	1e+12	NDD	1.0694	1.057	-0.0124
553	5e+12	NDD	1.0595	1.05	-0.0095
554	5e+12	NDD	1.0438	1.0325	-0.0113
555	5e+12	NDD	1.1033	1.0898	-0.0135
556	1e+13	NDD	1.0925	1.081	-0.0115
557	1e+13	NDD	1.0546	1.0435	-0.0111
558	1e+13	NDD	1.0502	1.0355	-0.0147
559	0	NDD, Ctrl	1.0533	1.0338	-0.0195

NDD vs Post - Pre Exposure Delta

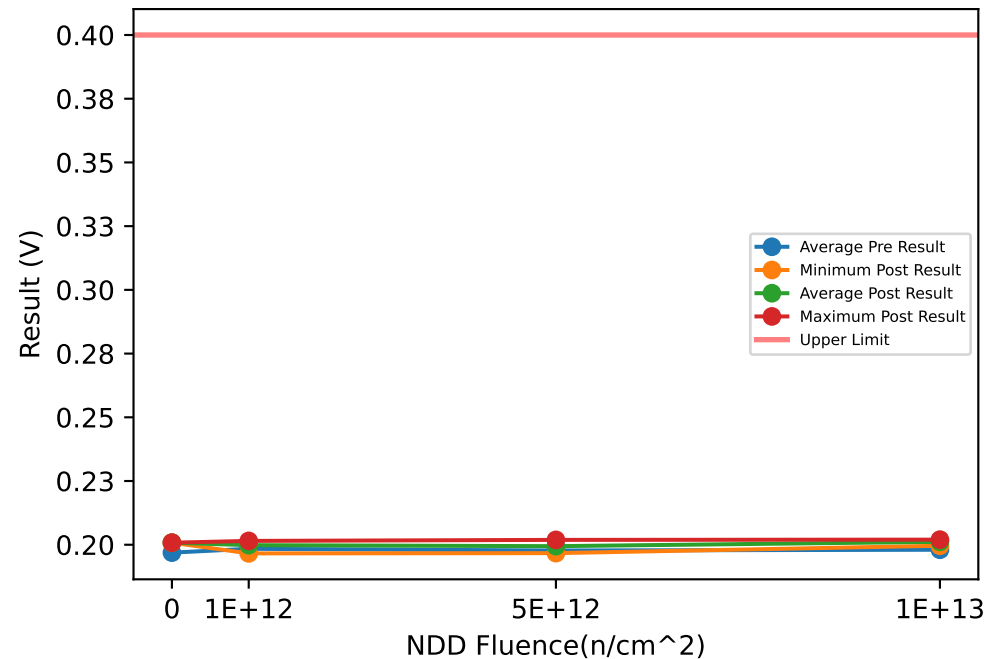


Test Statistics (MOhms)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0533	1.0533	1.0533		1.0338	1.0338	1.0338		-0.0195	-0.0195	-0.0195	
1e+12	1.0604	1.078	1.1043	0.023188	1.0434	1.0628	1.0881	0.022914	-0.017	-0.0152	-0.0124	0.0024576
5e+12	1.0438	1.0689	1.1033	0.030836	1.0325	1.0574	1.0898	0.029364	-0.0135	-0.011433	-0.0095	0.0020033
1e+13	1.0502	1.0658	1.0925	0.023256	1.0355	1.0533	1.081	0.024292	-0.0147	-0.012433	-0.0111	0.0019732

Device Test: 106.0 V_PGOOD_OL(PGOOD Logic Low Outupt)

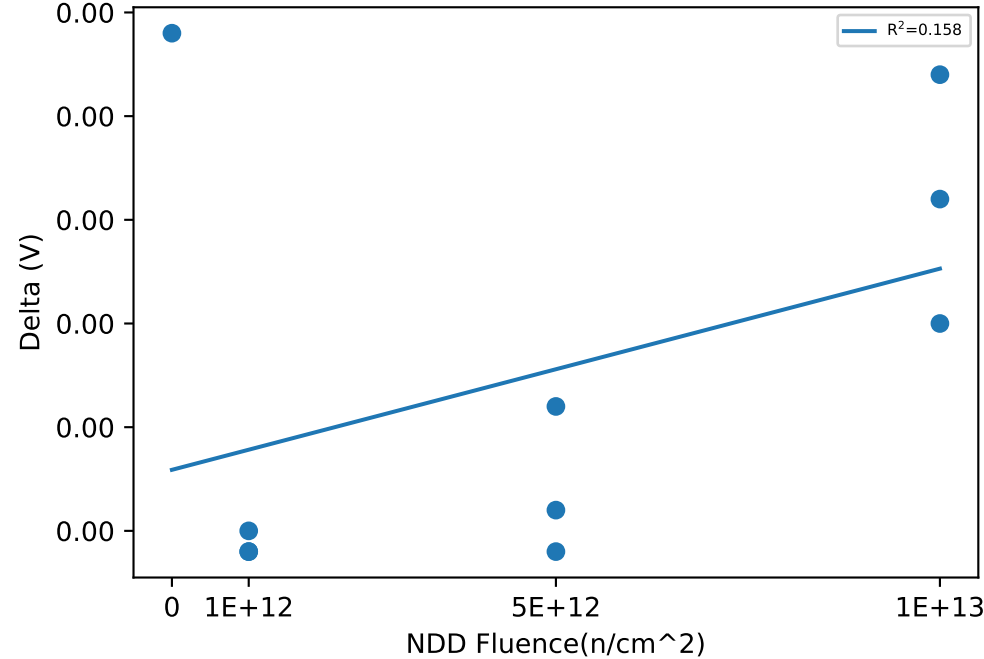
NDD vs Result Stats



Test Results (Upper Limit = 0.4 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	0.2	0.2014	0.0014
551	1e+12	NDD	0.1952	0.1966	0.0014
552	1e+12	NDD	0.2	0.2015	0.0015
553	5e+12	NDD	0.1976	0.1997	0.0021
554	5e+12	NDD	0.2003	0.2019	0.0016
555	5e+12	NDD	0.1953	0.1967	0.0014
556	1e+13	NDD	0.1993	0.2018	0.0025
557	1e+13	NDD	0.1965	0.1996	0.0031
558	1e+13	NDD	0.1983	0.202	0.0037
559	0	NDD, Ctrl	0.1969	0.2008	0.0039

NDD vs Post - Pre Exposure Delta

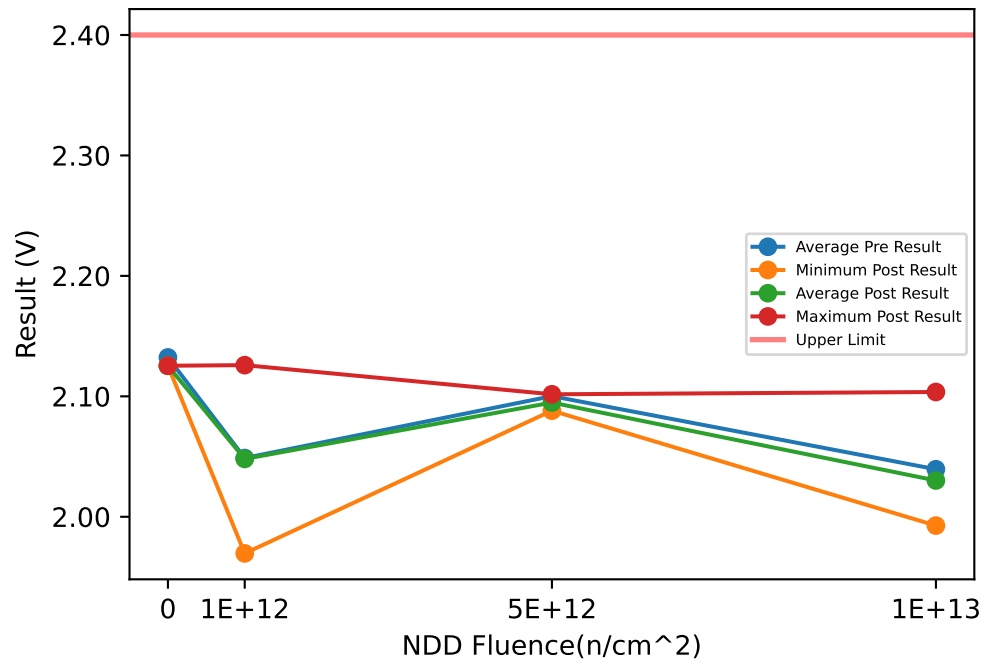


Test Statistics (V)

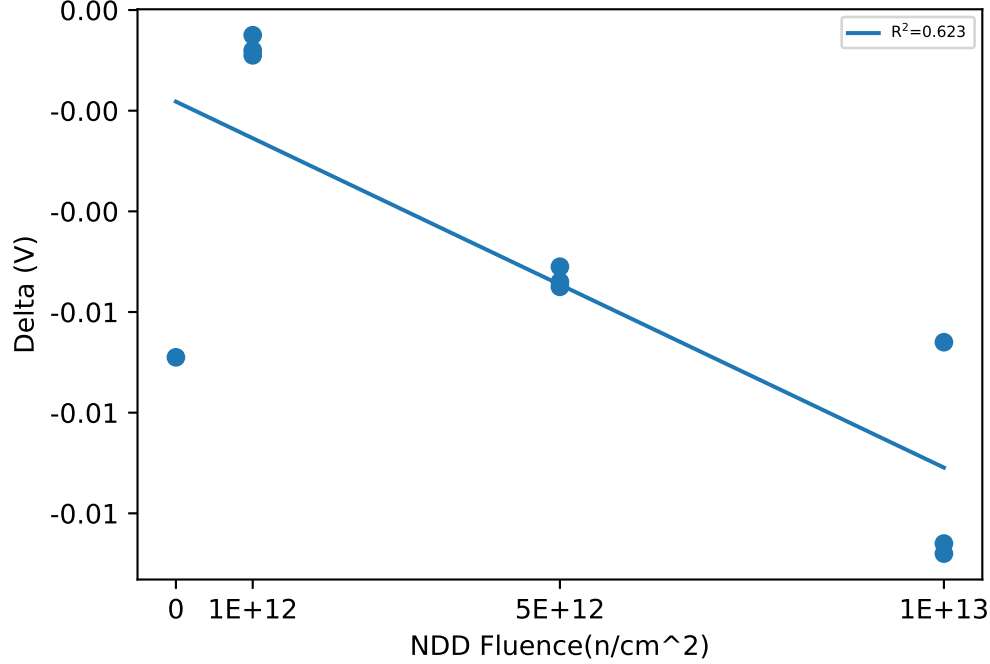
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1969	0.1969	0.1969		0.2008	0.2008	0.2008		0.0039	0.0039	0.0039	
1e+12	0.1952	0.1984	0.2	0.0027713	0.1966	0.19983	0.2015	0.0028006	0.0014	0.0014333	0.0015	5.7735e-05
5e+12	0.1953	0.19773	0.2003	0.0025027	0.1967	0.19943	0.2019	0.0026102	0.0014	0.0017	0.0021	0.00036056
1e+13	0.1965	0.19803	0.1993	0.0014189	0.1996	0.20113	0.202	0.0013317	0.0025	0.0031	0.0037	0.0006

Device Test: 106.1 V_BP5L_MIN_FOR_PGOOD(Min BP5L for Valid PGOOD)

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 2.4 (V))

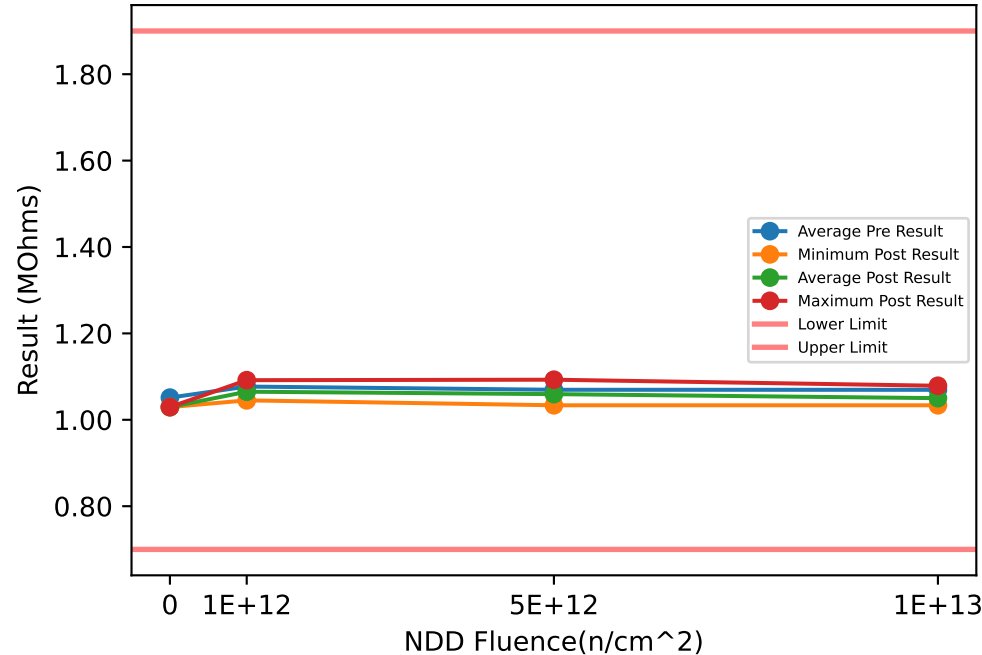
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	2.1267	2.1259	-0.0008
551	1e+12	NDD	1.9705	1.9696	-0.0009
552	1e+12	NDD	2.0491	2.0486	-0.0005
553	5e+12	NDD	2.0936	2.0881	-0.0055
554	5e+12	NDD	2.1068	2.1017	-0.0051
555	5e+12	NDD	2.1001	2.0947	-0.0054
556	1e+13	NDD	2.0049	1.9941	-0.0108
557	1e+13	NDD	2.1142	2.1036	-0.0106
558	1e+13	NDD	1.9993	1.9927	-0.0066
559	0	NDD, Ctrl	2.1323	2.1254	-0.0069

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.1323	2.1323	2.1323		2.1254	2.1254	2.1254		-0.0069	-0.0069	-0.0069	
1e+12	1.9705	2.0488	2.1267	0.078101	1.9696	2.048	2.1259	0.078152	-0.0009	-0.00073333	-0.0005	0.00020817
5e+12	2.0936	2.1002	2.1068	0.0066003	2.0881	2.0948	2.1017	0.006801	-0.0055	-0.0053333	-0.0051	0.00020817
1e+13	1.9993	2.0395	2.1142	0.064782	1.9927	2.0301	2.1036	0.063628	-0.0108	-0.0093333	-0.0066	0.0023692

Device Test: 106.2 I_PGOOD_PD_RES(PGOOD Internal Resistance VIN_12V)

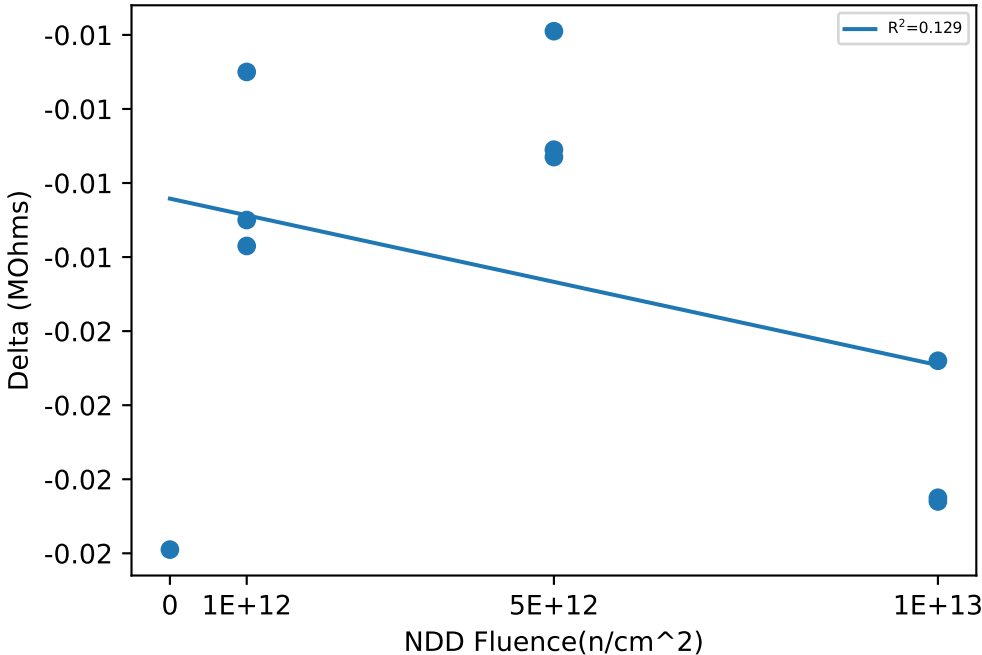
NDD vs Result Stats



Test Results (Lower Limit = 0.7, Upper Limit = 1.9 (MOhms))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	1.0587	1.045	-0.0137
551	1e+12	NDD	1.1047	1.0917	-0.013
552	1e+12	NDD	1.0674	1.0584	-0.009
553	5e+12	NDD	1.0629	1.0518	-0.0111
554	5e+12	NDD	1.0449	1.0336	-0.0113
555	5e+12	NDD	1.1007	1.0928	-0.0079
556	1e+13	NDD	1.0993	1.0788	-0.0205
557	1e+13	NDD	1.0585	1.0379	-0.0206
558	1e+13	NDD	1.0504	1.0336	-0.0168
559	0	NDD, Ctrl	1.0513	1.0294	-0.0219

NDD vs Post - Pre Exposure Delta

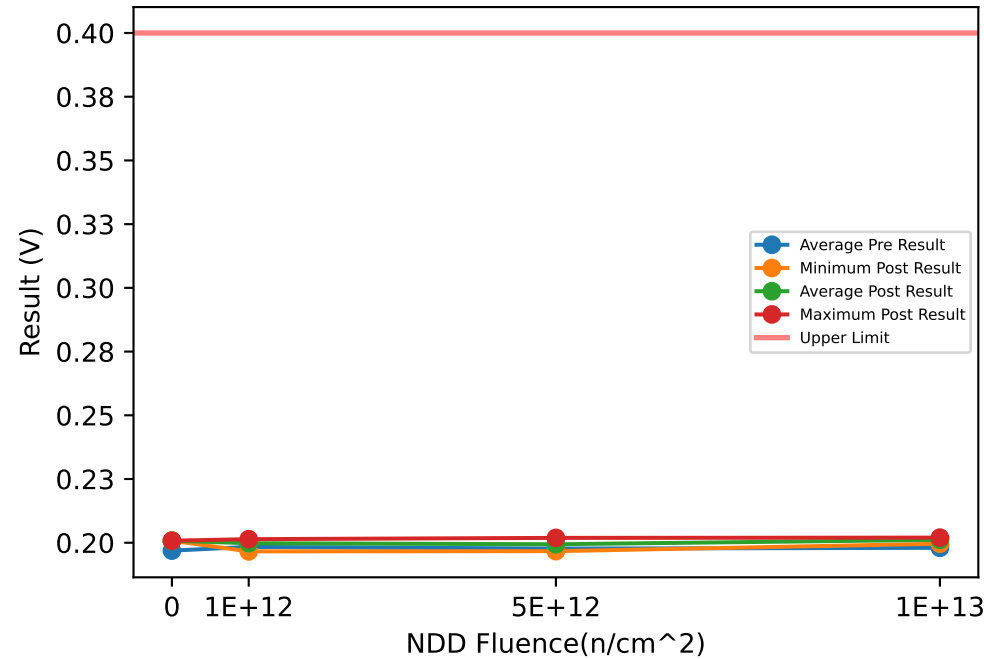


Test Statistics (MOhms)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0513	1.0513	1.0513		1.0294	1.0294	1.0294		-0.0219	-0.0219	-0.0219	
1e+12	1.0587	1.0769	1.1047	0.024437	1.045	1.065	1.0917	0.024046	-0.0137	-0.0119	-0.009	0.0025357
5e+12	1.0449	1.0695	1.1007	0.028479	1.0336	1.0594	1.0928	0.030323	-0.0113	-0.0101	-0.0079	0.0019079
1e+13	1.0504	1.0694	1.0993	0.026209	1.0336	1.0501	1.0788	0.024948	-0.0206	-0.0193	-0.0168	0.0021656

Device Test: 107.0 V_PGOOD_OL(PGOOD Logic Low Outupt)

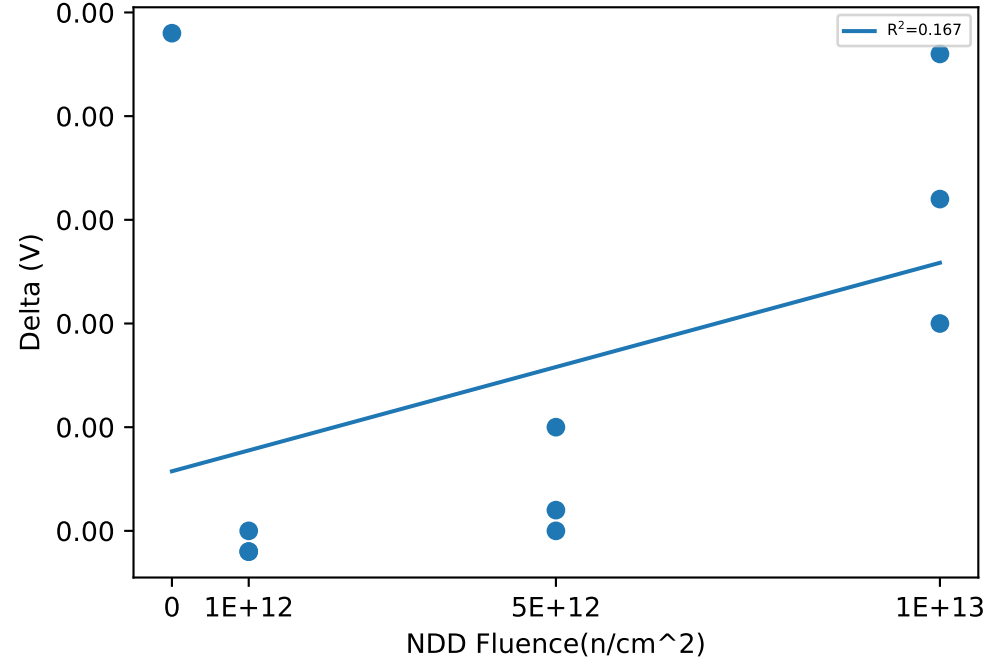
NDD vs Result Stats



Test Results (Upper Limit = 0.4 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	0.1999	0.2014	0.0015
551	1e+12	NDD	0.1952	0.1966	0.0014
552	1e+12	NDD	0.2	0.2014	0.0014
553	5e+12	NDD	0.1976	0.1996	0.002
554	5e+12	NDD	0.2003	0.2019	0.0016
555	5e+12	NDD	0.1952	0.1967	0.0015
556	1e+13	NDD	0.1993	0.2018	0.0025
557	1e+13	NDD	0.1965	0.1996	0.0031
558	1e+13	NDD	0.1982	0.202	0.0038
559	0	NDD, Ctrl	0.1969	0.2008	0.0039

NDD vs Post - Pre Exposure Delta

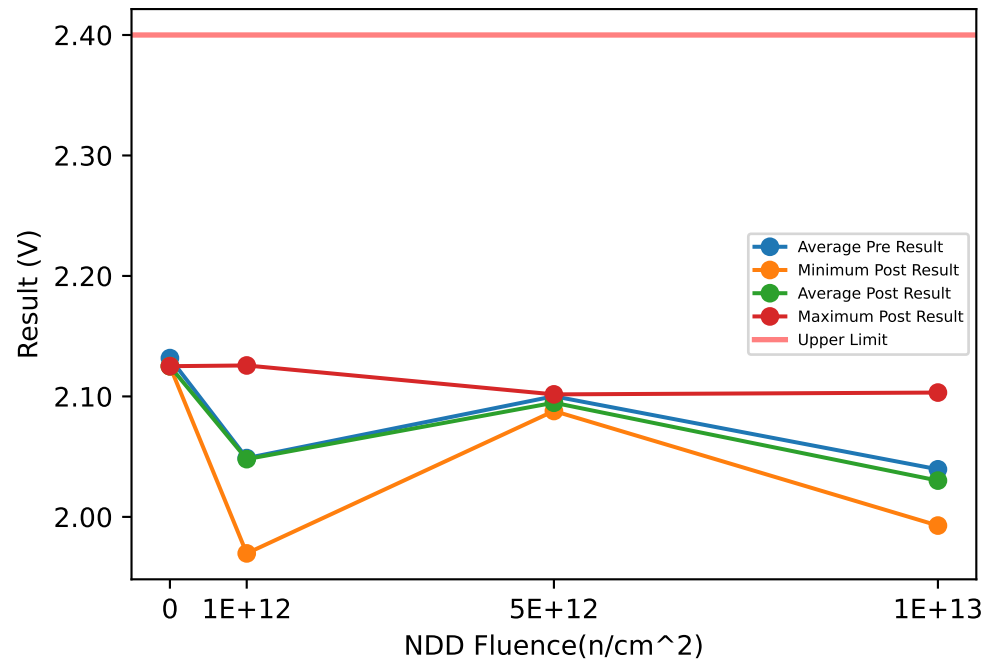


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1969	0.1969	0.1969		0.2008	0.2008	0.2008		0.0039	0.0039	0.0039	
1e+12	0.1952	0.19837	0.2	0.0027429	0.1966	0.1998	0.2014	0.0027713	0.0014	0.0014333	0.0015	5.7735e-05
5e+12	0.1952	0.1977	0.2003	0.0025515	0.1967	0.1994	0.2019	0.0026058	0.0015	0.0017	0.002	0.00026458
1e+13	0.1965	0.198	0.1993	0.0014107	0.1996	0.20113	0.202	0.0013317	0.0025	0.0031333	0.0038	0.00065064

Device Test: 107.1 V_BP5L_MIN_FOR_PGOOD(Min BP5L for Valid PGOOD)

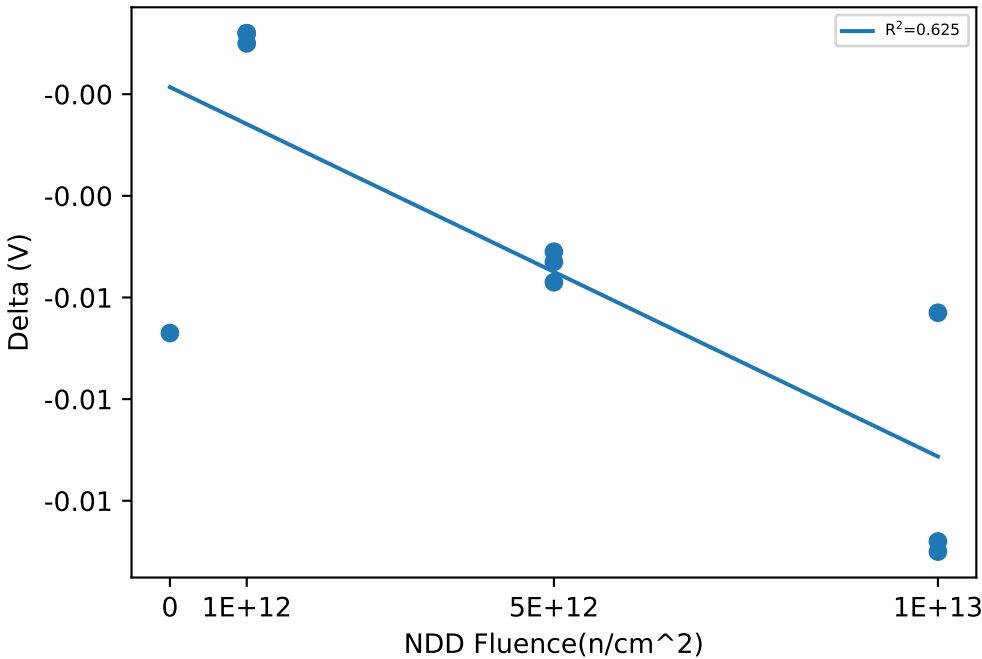
NDD vs Result Stats



Test Results (Upper Limit = 2.4 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	2.1265	2.1257	-0.0008
551	1e+12	NDD	1.9705	1.9697	-0.0008
552	1e+12	NDD	2.0494	2.0484	-0.001
553	5e+12	NDD	2.0936	2.0879	-0.0057
554	5e+12	NDD	2.1068	2.1017	-0.0051
555	5e+12	NDD	2.1	2.0947	-0.0053
556	1e+13	NDD	2.0052	1.9944	-0.0108
557	1e+13	NDD	2.1142	2.1032	-0.011
558	1e+13	NDD	1.9991	1.9928	-0.0063
559	0	NDD, Ctrl	2.1318	2.1251	-0.0067

NDD vs Post - Pre Exposure Delta

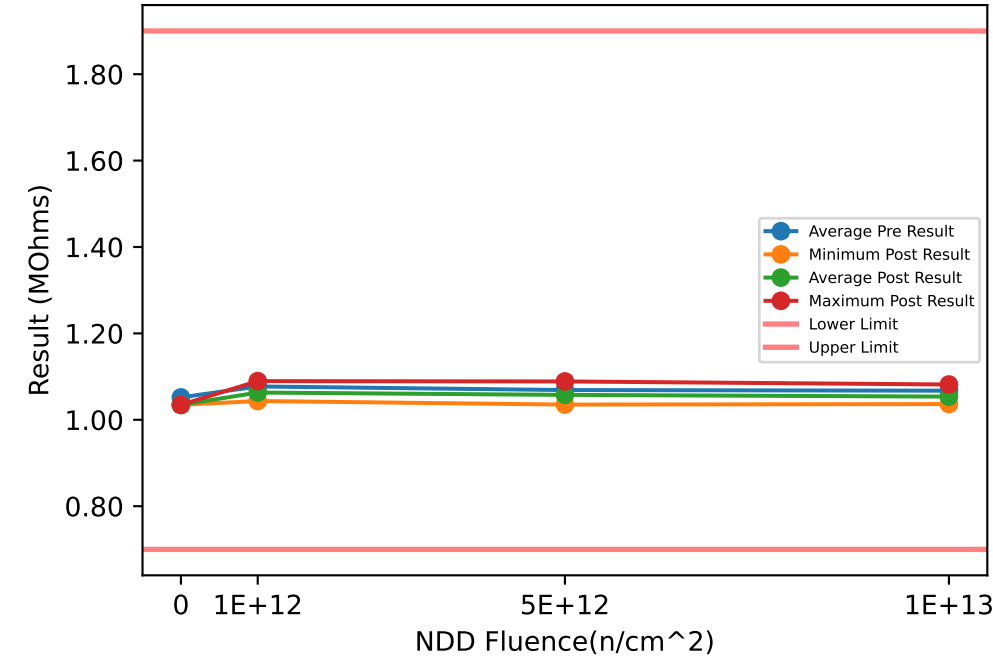


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.1318	2.1318	2.1318		2.1251	2.1251	2.1251		-0.0067	-0.0067	-0.0067	
1e+12	1.9705	2.0488	2.1265	0.078002	1.9697	2.0479	2.1257	0.078001	-0.001	-0.00086667	-0.0008	0.00011547
5e+12	2.0936	2.1001	2.1068	0.006601	2.0879	2.0948	2.1017	0.0069002	-0.0057	-0.0053667	-0.0051	0.00030551
1e+13	1.9991	2.0395	2.1142	0.064764	1.9928	2.0301	2.1032	0.063283	-0.011	-0.0093667	-0.0063	0.0026577

Device Test: 107.2 I_PGOOD_PD_RES(PGOOD Internal Resistance VIN_14V)

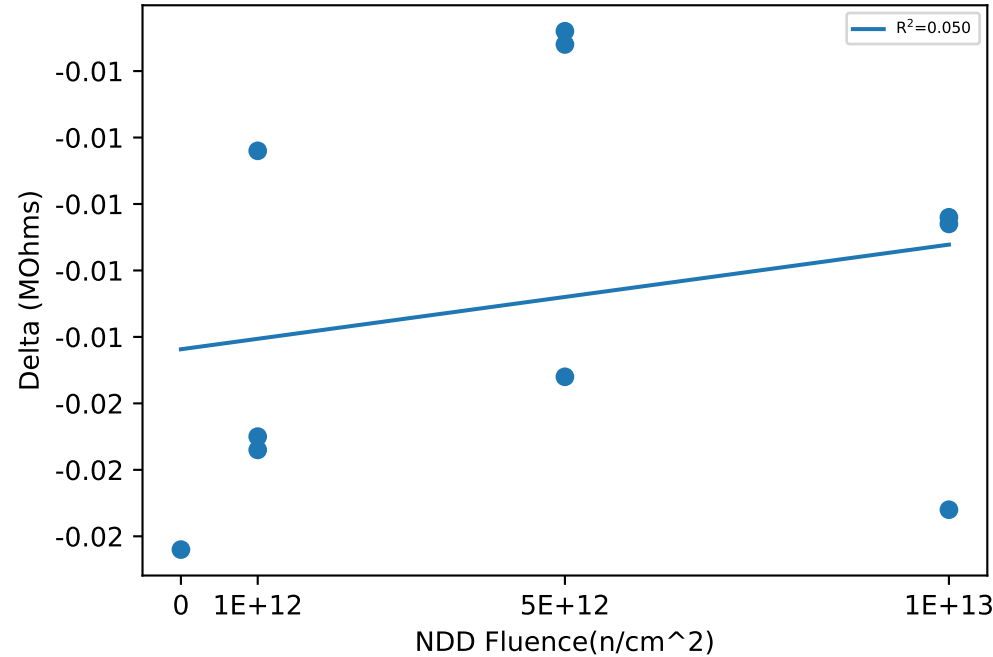
NDD vs Result Stats



Test Results (Lower Limit = 0.7, Upper Limit = 1.9 (MOhms))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	1.059	1.0435	-0.0155
551	1e+12	NDD	1.1052	1.0895	-0.0157
552	1e+12	NDD	1.0674	1.0562	-0.0112
553	5e+12	NDD	1.0586	1.049	-0.0096
554	5e+12	NDD	1.0446	1.0352	-0.0094
555	5e+12	NDD	1.1034	1.0888	-0.0146
556	1e+13	NDD	1.094	1.0817	-0.0123
557	1e+13	NDD	1.0551	1.0429	-0.0122
558	1e+13	NDD	1.053	1.0364	-0.0166
559	0	NDD, Ctrl	1.0518	1.0346	-0.0172

NDD vs Post - Pre Exposure Delta

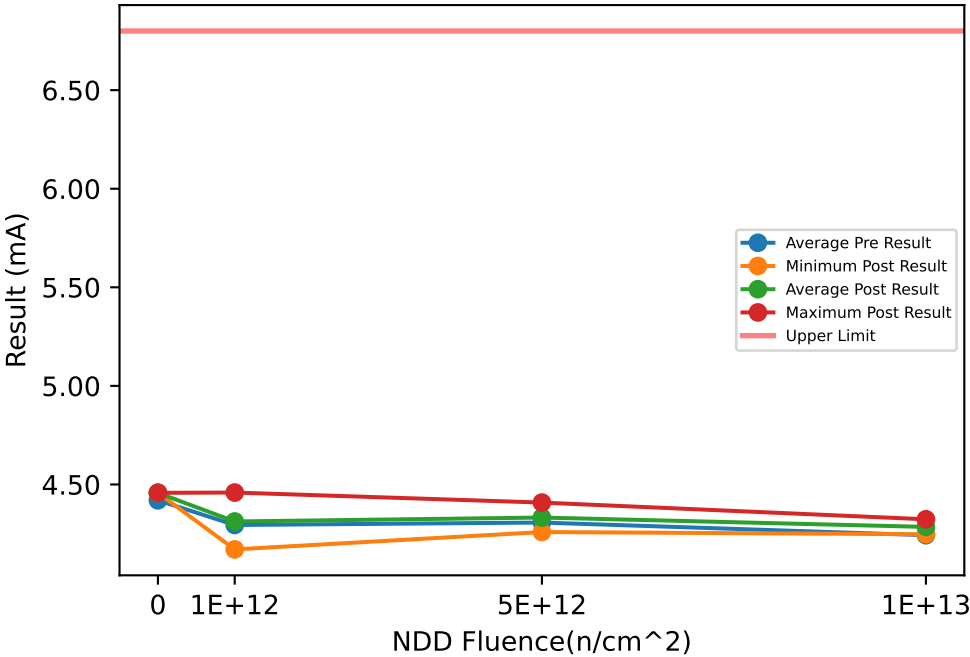


Test Statistics (MOhms)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0518	1.0518	1.0518		1.0346	1.0346	1.0346		-0.0172	-0.0172	-0.0172	
1e+12	1.059	1.0772	1.1052	0.02461	1.0435	1.0631	1.0895	0.023756	-0.0157	-0.014133	-0.0112	0.0025423
5e+12	1.0446	1.0689	1.1034	0.030715	1.0352	1.0577	1.0888	0.027831	-0.0146	-0.0112	-0.0094	0.0029462
1e+13	1.053	1.0674	1.094	0.023089	1.0364	1.0537	1.0817	0.024494	-0.0166	-0.0137	-0.0122	0.002512

Device Test: 35.0 IQ_LS_PWM(Iq LS VIN PWM VIN_10V)

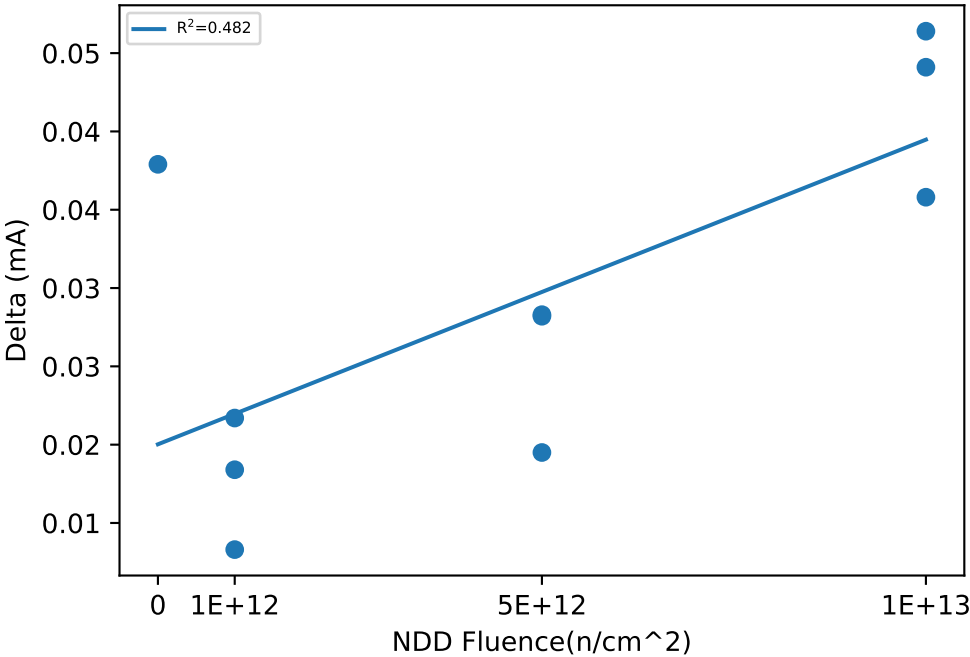
NDD vs Result Stats



Test Results (Upper Limit = 6.8 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.2888	4.3072	0.0184
551	1e+12	NDD	4.1574	4.1707	0.0133
552	1e+12	NDD	4.4374	4.4591	0.0217
553	5e+12	NDD	4.3016	4.3298	0.0282
554	5e+12	NDD	4.3887	4.4082	0.0195
555	5e+12	NDD	4.2304	4.2587	0.0283
556	1e+13	NDD	4.2371	4.2835	0.0464
557	1e+13	NDD	4.2035	4.2476	0.0441
558	1e+13	NDD	4.2876	4.3234	0.0358
559	0	NDD, Ctrl	4.4197	4.4576	0.0379

NDD vs Post - Pre Exposure Delta

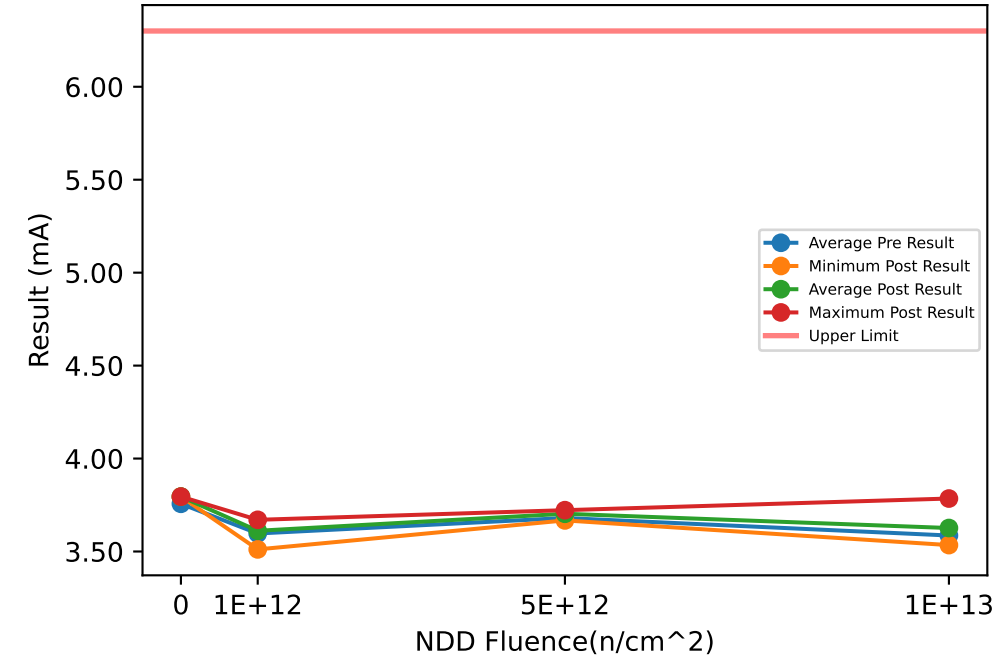


Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.4197	4.4197	4.4197		4.4576	4.4576	4.4576		0.0379	0.0379	0.0379	
1e+12	4.1574	4.2945	4.4374	0.14009	4.1707	4.3123	4.4591	0.14427	0.0133	0.0178	0.0217	0.004232
5e+12	4.2304	4.3069	4.3887	0.079283	4.2587	4.3322	4.4082	0.07478	0.0195	0.025333	0.0283	0.0050521
1e+13	4.2035	4.2427	4.2876	0.042332	4.2476	4.2848	4.3234	0.037918	0.0358	0.0421	0.0464	0.0055758

Device Test: 35.1 IQ_HS_PWM(Iq HS BOOT PWM VIN_10V)

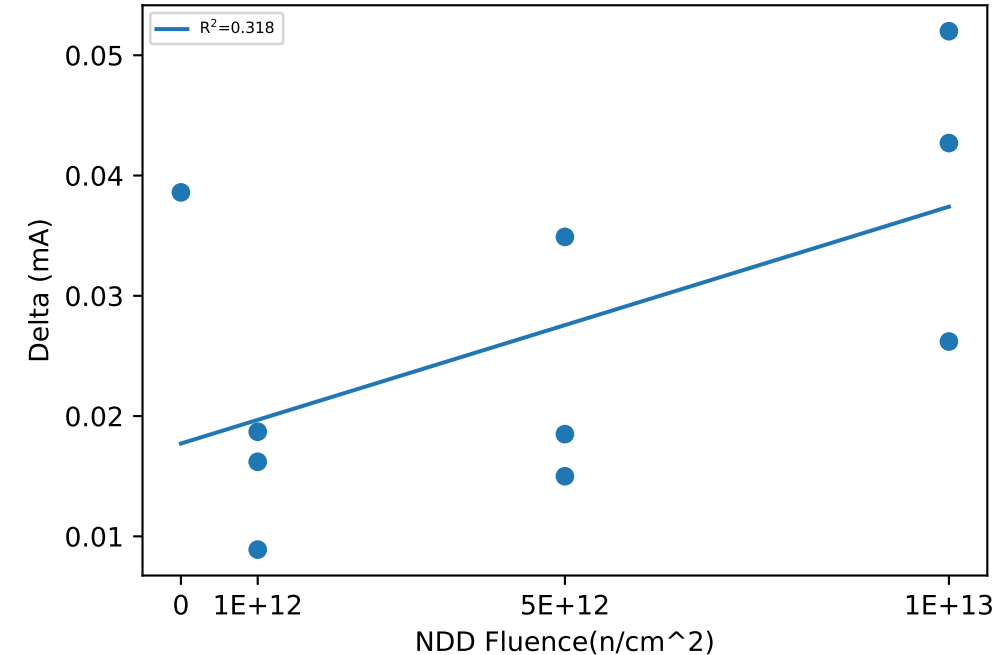
NDD vs Result Stats



Test Results (Upper Limit = 6.3 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	3.6365	3.6527	0.0162
551	1e+12	NDD	3.4926	3.5113	0.0187
552	1e+12	NDD	3.6615	3.6704	0.0089
553	5e+12	NDD	3.6846	3.7195	0.0349
554	5e+12	NDD	3.7038	3.7223	0.0185
555	5e+12	NDD	3.6522	3.6672	0.015
556	1e+13	NDD	3.5083	3.5345	0.0262
557	1e+13	NDD	3.5169	3.5596	0.0427
558	1e+13	NDD	3.7329	3.7849	0.052
559	0	NDD, Ctrl	3.7566	3.7952	0.0386

NDD vs Post - Pre Exposure Delta

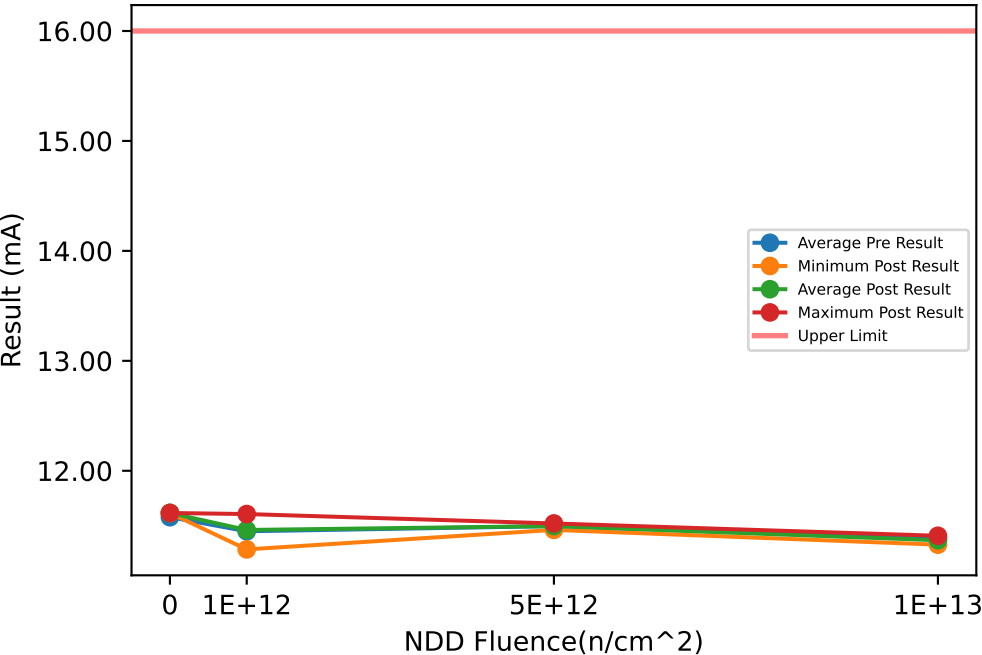


Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7566	3.7566	3.7566		3.7952	3.7952	3.7952		0.0386	0.0386	0.0386	
1e+12	3.4926	3.5969	3.6615	0.091159	3.5113	3.6115	3.6704	0.087197	0.0089	0.0146	0.0187	0.0050922
5e+12	3.6522	3.6802	3.7038	0.02608	3.6672	3.703	3.7223	0.031035	0.015	0.0228	0.0349	0.010624
1e+13	3.5083	3.586	3.7329	0.12726	3.5345	3.6263	3.7849	0.1379	0.0262	0.0403	0.052	0.013066

Device Test: 35.10 I_OP_LS_PWM_2MHZ(lop LS VIN PWM 2MHz VIN_10V)

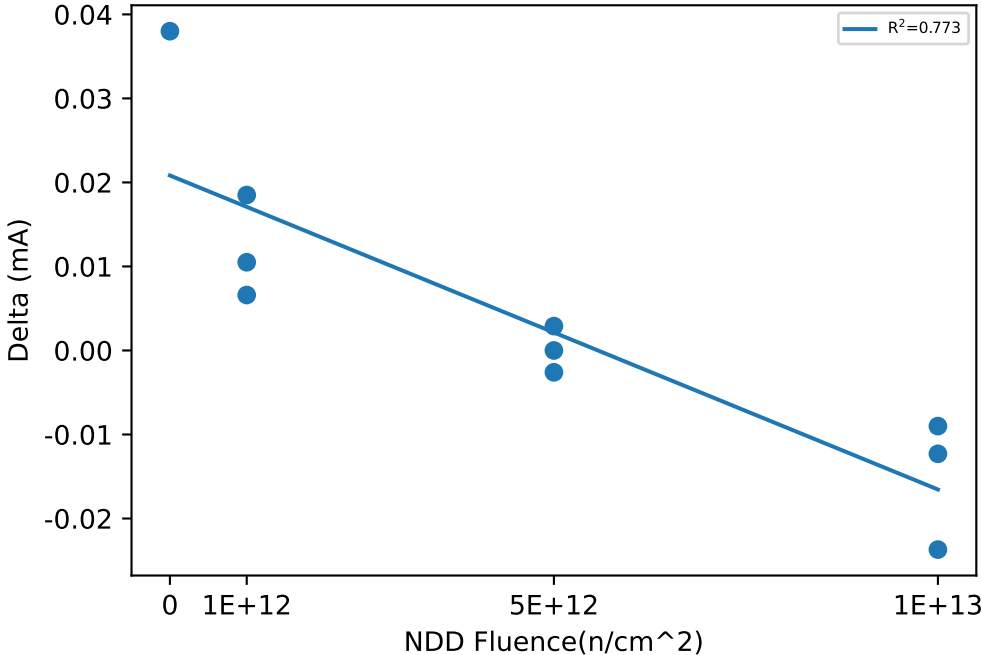
NDD vs Result Stats



Test Results (Upper Limit = 16.0 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	11.487	11.494	0.0066
551	1e+12	NDD	11.274	11.285	0.0105
552	1e+12	NDD	11.588	11.606	0.0185
553	5e+12	NDD	11.504	11.507	0.0029
554	5e+12	NDD	11.524	11.521	-0.0026
555	5e+12	NDD	11.462	11.462	0
556	1e+13	NDD	11.34	11.328	-0.0123
557	1e+13	NDD	11.418	11.409	-0.009
558	1e+13	NDD	11.391	11.367	-0.0237
559	0	NDD, Ctrl	11.578	11.616	0.038

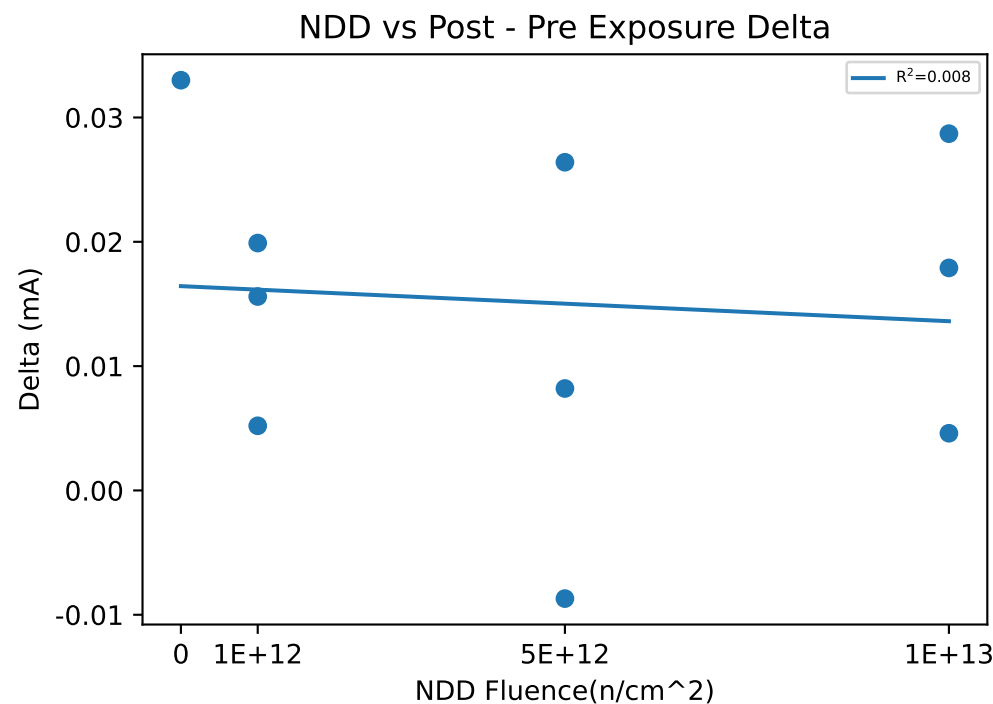
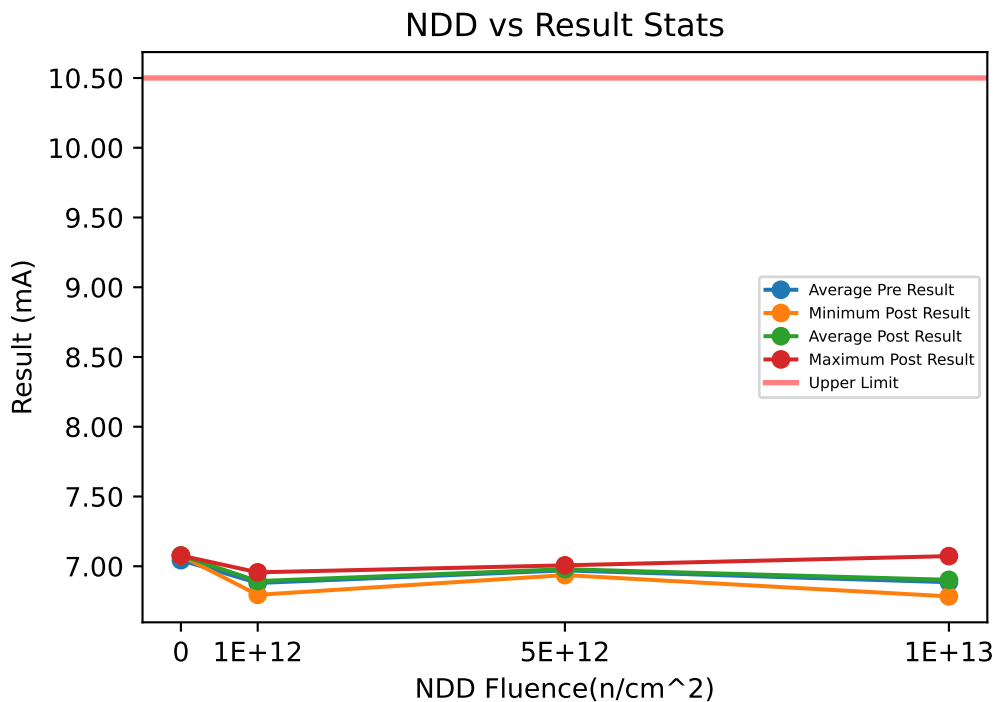
NDD vs Post - Pre Exposure Delta



Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	11.578	11.578	11.578		11.616	11.616	11.616		0.038	0.038	0.038	
1e+12	11.274	11.45	11.588	0.16004	11.285	11.462	11.606	0.16313	0.0066	0.011867	0.0185	0.0060666
5e+12	11.462	11.497	11.524	0.031233	11.462	11.497	11.521	0.03058	-0.0026	0.0001	0.0029	0.0027514
1e+13	11.34	11.383	11.418	0.039285	11.328	11.368	11.409	0.040358	-0.0237	-0.015	-0.009	0.007713

Device Test: 35.11 I_OP_HS_PWM_2MHZ(Iop HS BOOT PWM 2MHz VIN_10V)



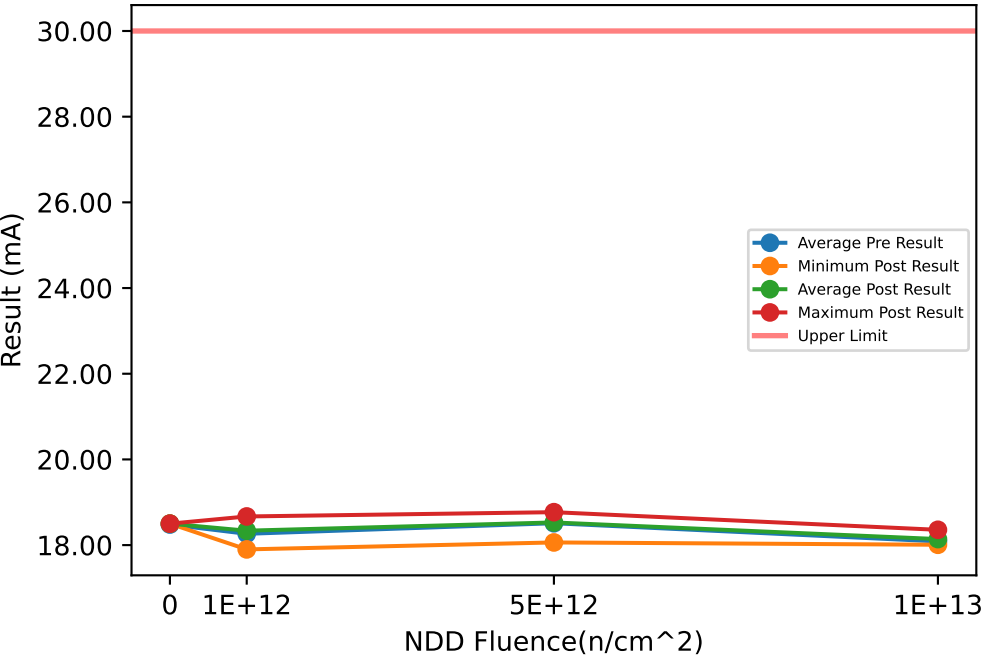
Test Results (Upper Limit = 10.5 (mA))					
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	6.914	6.9296	0.0156
551	1e+12	NDD	6.7751	6.795	0.0199
552	1e+12	NDD	6.9512	6.9564	0.0052
553	5e+12	NDD	6.9801	7.0065	0.0264
554	5e+12	NDD	6.9854	6.9936	0.0082
555	5e+12	NDD	6.9453	6.9366	-0.0087
556	1e+13	NDD	6.7793	6.7839	0.0046
557	1e+13	NDD	6.8338	6.8517	0.0179
558	1e+13	NDD	7.0439	7.0726	0.0287
559	0	NDD, Ctrl	7.0436	7.0766	0.033

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0436	7.0436	7.0436		7.0766	7.0766	7.0766		0.033	0.033	0.033	
1e+12	6.7751	6.8801	6.9512	0.092815	6.795	6.8937	6.9564	0.086492	0.0052	0.013567	0.0199	0.007558
5e+12	6.9453	6.9703	6.9854	0.021784	6.9366	6.9789	7.0065	0.037196	-0.0087	0.0086333	0.0264	0.017554
1e+13	6.7793	6.8857	7.0439	0.13972	6.7839	6.9027	7.0726	0.15096	0.0046	0.017067	0.0287	0.012072

Device Test: 35.12 I_OP_LS_PWM_5MHZ(lop LS VIN PWM 5MHz VIN_10V)

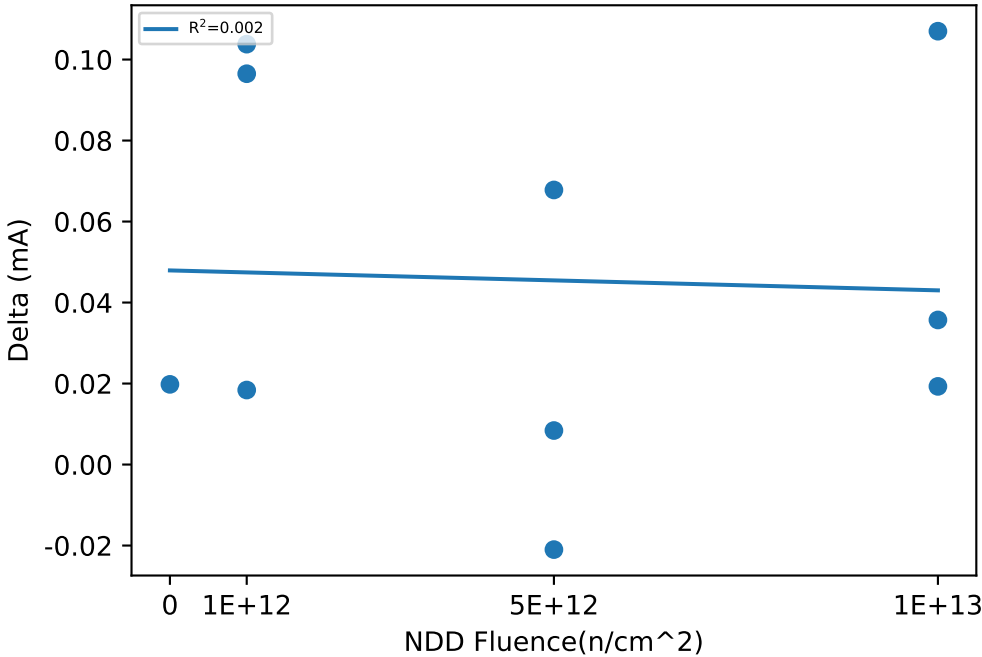
NDD vs Result Stats



Test Results (Upper Limit = 30.0 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	18.337	18.441	0.1038
551	1e+12	NDD	17.881	17.9	0.0184
552	1e+12	NDD	18.572	18.669	0.0965
553	5e+12	NDD	18.748	18.756	0.0084
554	5e+12	NDD	18.79	18.768	-0.021
555	5e+12	NDD	17.994	18.062	0.0678
556	1e+13	NDD	18.338	18.357	0.0193
557	1e+13	NDD	17.95	18.057	0.107
558	1e+13	NDD	17.972	18.008	0.0357
559	0	NDD, Ctrl	18.481	18.5	0.0198

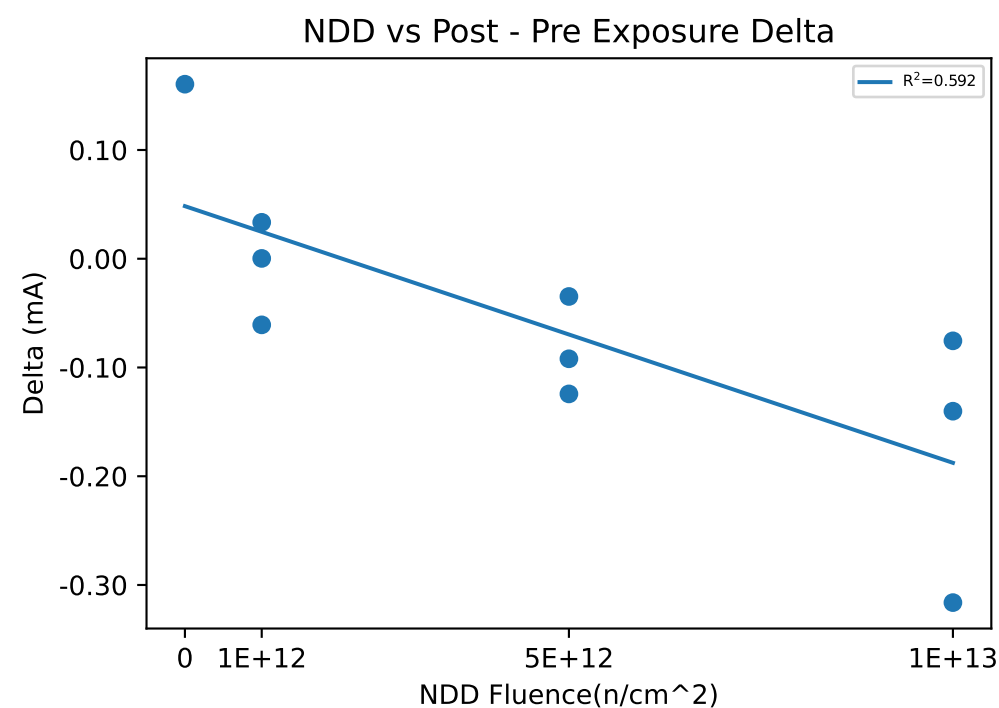
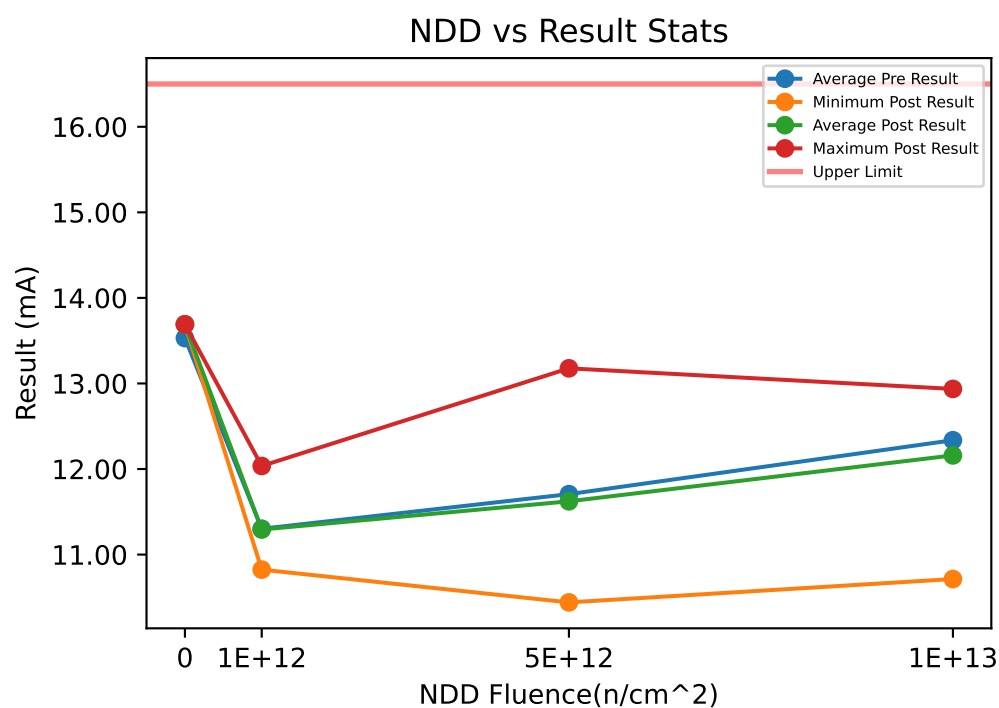
NDD vs Post - Pre Exposure Delta



Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	18.481	18.481	18.481		18.5	18.5	18.5		0.0198	0.0198	0.0198	
1e+12	17.881	18.264	18.572	0.35118	17.9	18.336	18.669	0.3949	0.0184	0.0729	0.1038	0.047339
5e+12	17.994	18.511	18.79	0.44758	18.062	18.529	18.768	0.40436	-0.021	0.0184	0.0678	0.045237
1e+13	17.95	18.087	18.338	0.21754	18.008	18.141	18.357	0.18882	0.0193	0.054	0.107	0.046626

Device Test: 35.13 I_OP_HS_PWM_5MHZ(Iop HS BOOT PWM 5MHz VIN_10V)



Test Results (Upper Limit = 16.5 (mA))

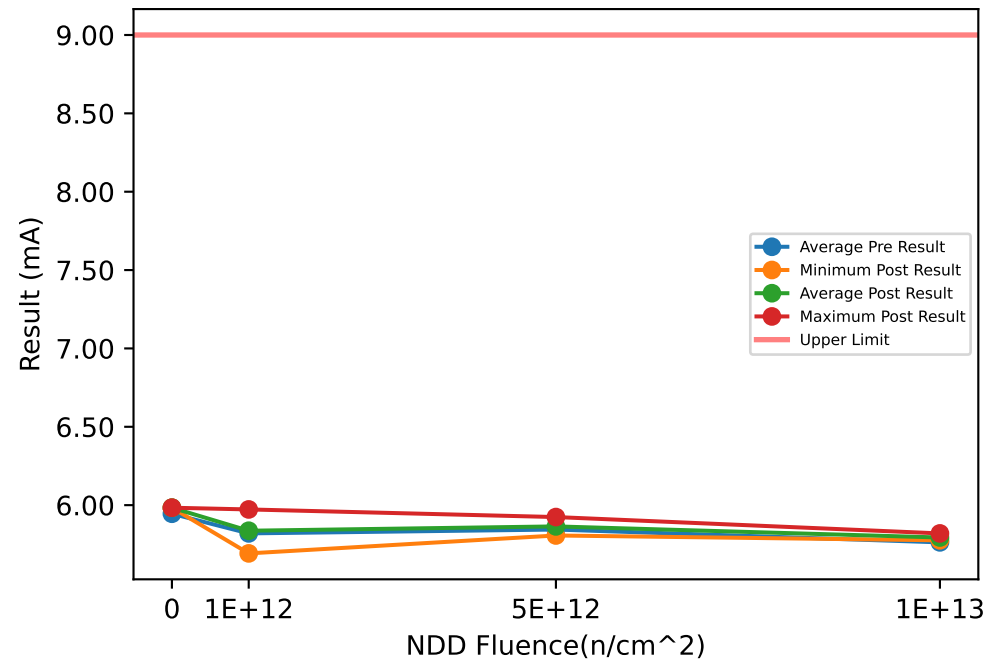
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	10.986	11.02	0.0335
551	1e+12	NDD	10.824	10.824	0.0003
552	1e+12	NDD	12.096	12.036	-0.0608
553	5e+12	NDD	11.342	11.25	-0.092
554	5e+12	NDD	10.476	10.441	-0.0347
555	5e+12	NDD	13.301	13.177	-0.1243
556	1e+13	NDD	10.79	10.714	-0.0755
557	1e+13	NDD	13.252	12.936	-0.3162
558	1e+13	NDD	12.967	12.827	-0.1402
559	0	NDD, Ctrl	13.53	13.691	0.1605

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	13.53	13.53	13.53		13.691	13.691	13.691		0.1605	0.1605	0.1605	
1e+12	10.824	11.302	12.096	0.69262	10.824	11.293	12.036	0.65038	-0.0608	-0.009	0.0335	0.047833
5e+12	10.476	11.706	13.301	1.4475	10.441	11.623	13.177	1.4055	-0.1243	-0.083667	-0.0347	0.045378
1e+13	10.79	12.337	13.252	1.3472	10.714	12.159	12.936	1.2527	-0.3162	-0.1773	-0.0755	0.12456

Device Test: 35.14 I_OP_LS_IIM_500KHZ_INTERLOCK(Iop LS VIN IIM Interlock 500kHz VIN_10V)

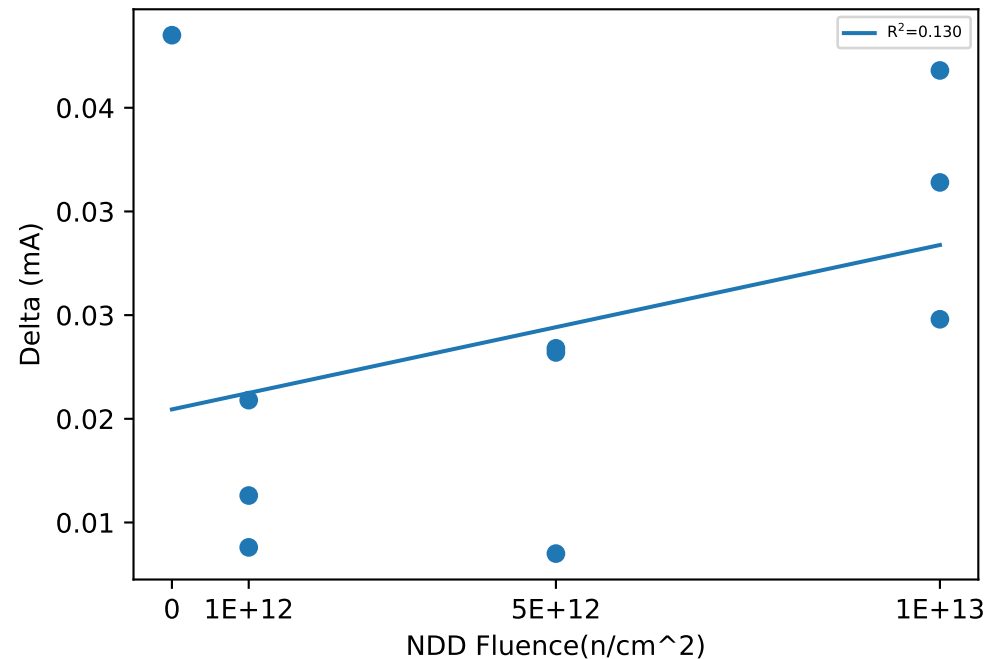
NDD vs Result Stats



Test Results (Upper Limit = 9.0 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	5.8292	5.8455	0.0163
551	1e+12	NDD	5.6783	5.6921	0.0138
552	1e+12	NDD	5.9517	5.9726	0.0209
553	5e+12	NDD	5.8395	5.8627	0.0232
554	5e+12	NDD	5.9105	5.924	0.0135
555	5e+12	NDD	5.783	5.8064	0.0234
556	1e+13	NDD	5.7487	5.7855	0.0368
557	1e+13	NDD	5.7442	5.7756	0.0314
558	1e+13	NDD	5.7948	5.8196	0.0248
559	0	NDD, Ctrl	5.9451	5.9836	0.0385

NDD vs Post - Pre Exposure Delta

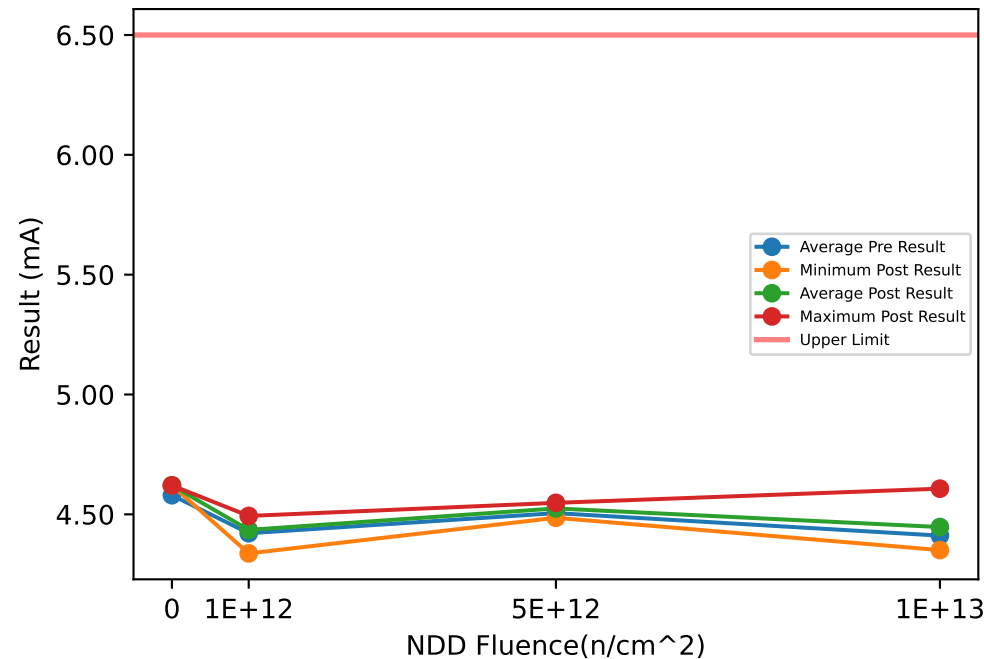


Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.9451	5.9451	5.9451		5.9836	5.9836	5.9836		0.0385	0.0385	0.0385	
1e+12	5.6783	5.8197	5.9517	0.13695	5.6921	5.8367	5.9726	0.14046	0.0138	0.017	0.0209	0.0036014
5e+12	5.783	5.8443	5.9105	0.063887	5.8064	5.8644	5.924	0.058818	0.0135	0.020033	0.0234	0.0056589
1e+13	5.7442	5.7626	5.7948	0.028005	5.7756	5.7936	5.8196	0.023083	0.0248	0.031	0.0368	0.00601

Device Test: 35.15 I_OP_HS_IIM_500KHZ_INTERLOCK(Iop HS BOOT IIM Interlock 500kHz VIN_10V)

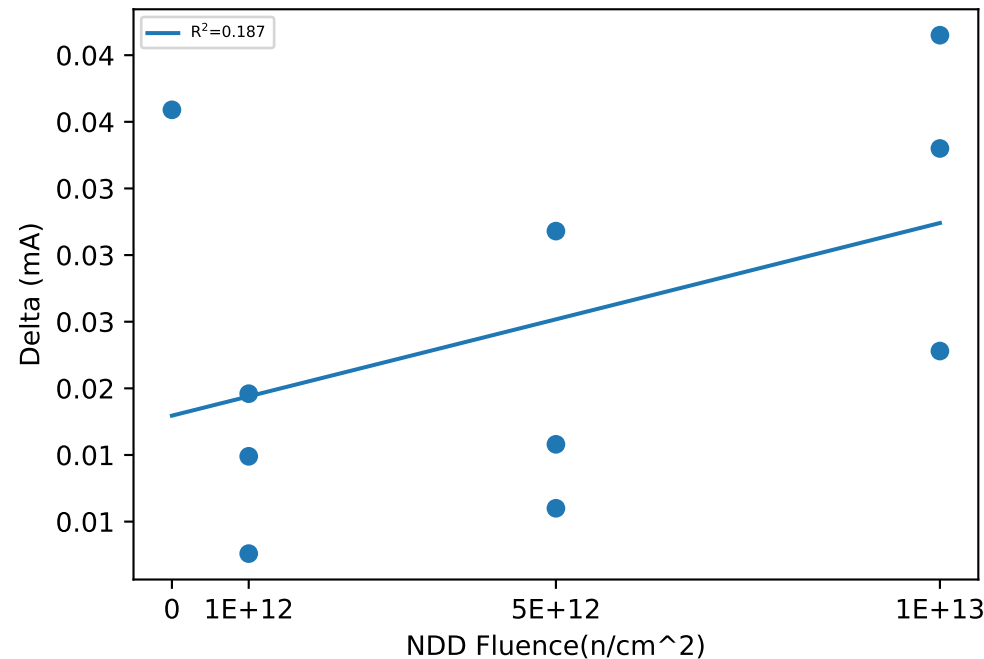
NDD vs Result Stats



Test Results (Upper Limit = 6.5 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.4601	4.475	0.0149
551	1e+12	NDD	4.3174	4.337	0.0196
552	1e+12	NDD	4.4857	4.4933	0.0076
553	5e+12	NDD	4.5086	4.5404	0.0318
554	5e+12	NDD	4.5321	4.5479	0.0158
555	5e+12	NDD	4.4746	4.4856	0.011
556	1e+13	NDD	4.328	4.3508	0.0228
557	1e+13	NDD	4.3449	4.3829	0.038
558	1e+13	NDD	4.5606	4.6071	0.0465
559	0	NDD, Ctrl	4.5798	4.6207	0.0409

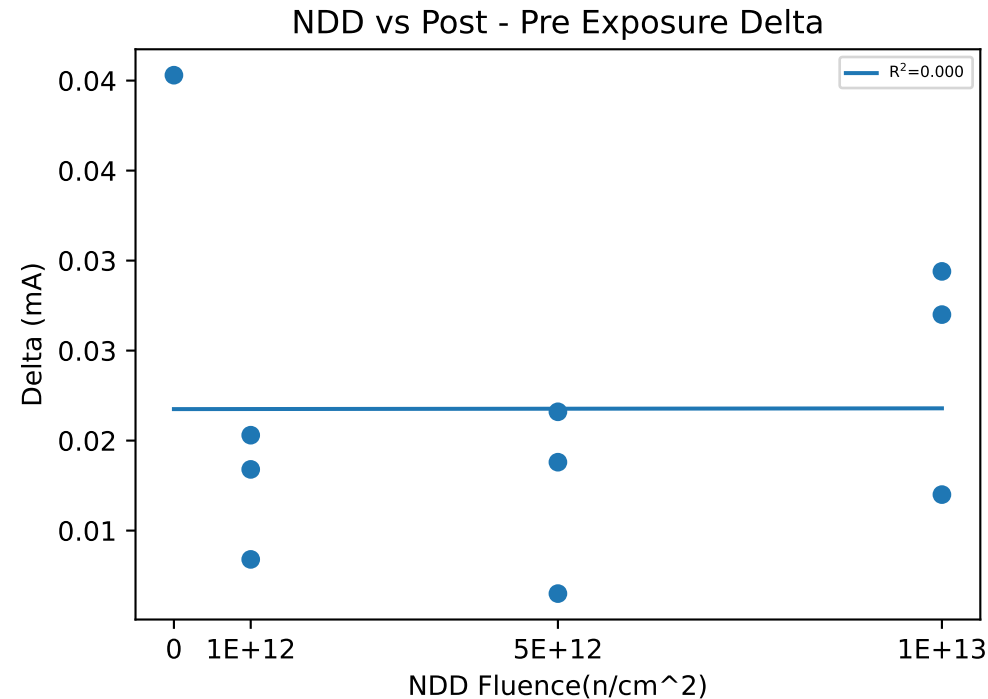
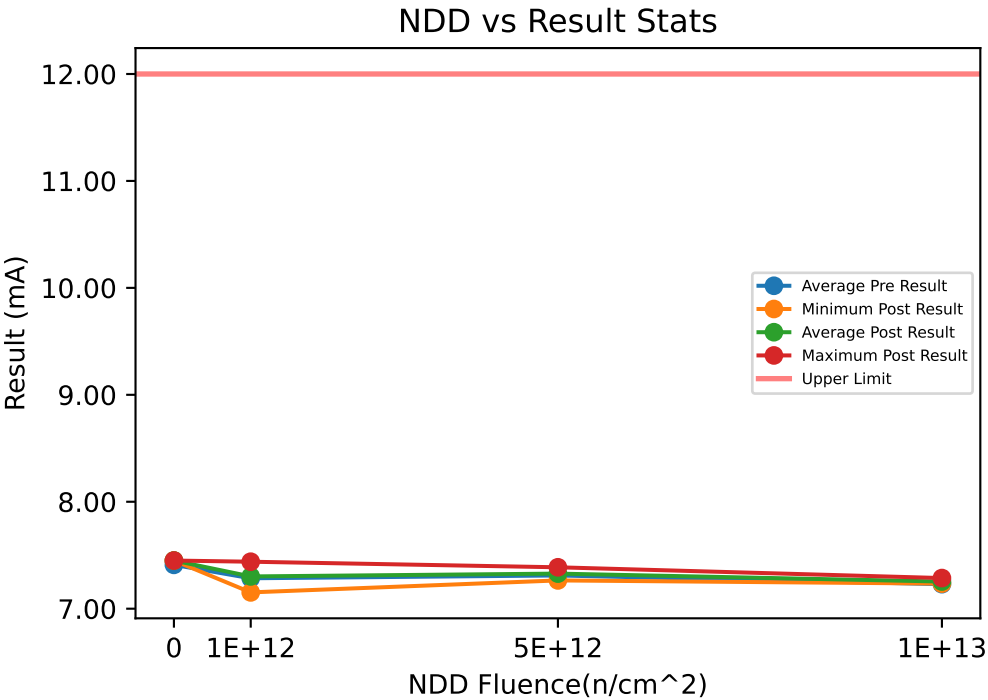
NDD vs Post - Pre Exposure Delta



Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.5798	4.5798	4.5798		4.6207	4.6207	4.6207		0.0409	0.0409	0.0409	
1e+12	4.3174	4.4211	4.4857	0.090686	4.337	4.4351	4.4933	0.085448	0.0076	0.014033	0.0196	0.0060468
5e+12	4.4746	4.5051	4.5321	0.028909	4.4856	4.5246	4.5479	0.034011	0.011	0.019533	0.0318	0.010891
1e+13	4.328	4.4112	4.5606	0.12969	4.3508	4.4469	4.6071	0.13963	0.0228	0.035767	0.0465	0.012007

Device Test: 35.16 I_OP_LS_IIM_1MHZ_INTERLOCK(Iop LS VIN IIM Interlock 1MHz VIN_10V)



Test Results (Upper Limit = 12.0 (mA))

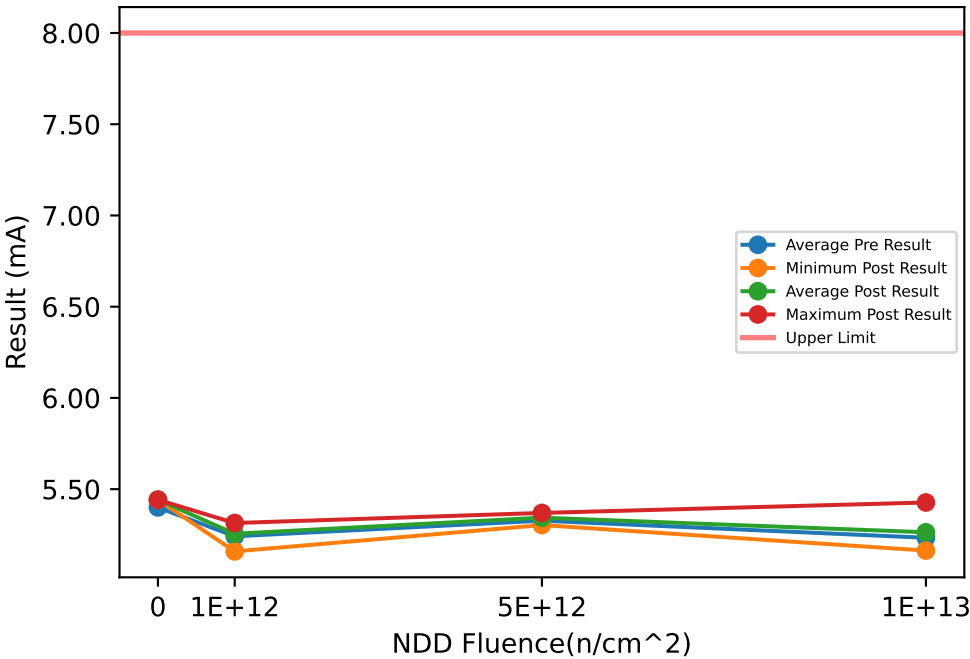
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	7.2951	7.3135	0.0184
551	1e+12	NDD	7.139	7.1524	0.0134
552	1e+12	NDD	7.419	7.4393	0.0203
553	5e+12	NDD	7.311	7.3326	0.0216
554	5e+12	NDD	7.3757	7.3872	0.0115
555	5e+12	NDD	7.2456	7.2644	0.0188
556	1e+13	NDD	7.2052	7.2346	0.0294
557	1e+13	NDD	7.2137	7.2407	0.027
558	1e+13	NDD	7.2695	7.2865	0.017
559	0	NDD, Ctrl	7.4099	7.4502	0.0403

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.4099	7.4099	7.4099		7.4502	7.4502	7.4502		0.0403	0.0403	0.0403	
1e+12	7.139	7.2844	7.419	0.14031	7.1524	7.3017	7.4393	0.14381	0.0134	0.017367	0.0203	0.0035642
5e+12	7.2456	7.3108	7.3757	0.06505	7.2644	7.3281	7.3872	0.061525	0.0115	0.0173	0.0216	0.0052144
1e+13	7.2052	7.2295	7.2695	0.034929	7.2346	7.2539	7.2865	0.028368	0.017	0.024467	0.0294	0.0065767

Device Test: 35.17 I_OP_HS_IIM_1MHZ_INTERLOCK(Iop HS BOOT IIM Interlock 1MHz VIN_10V)

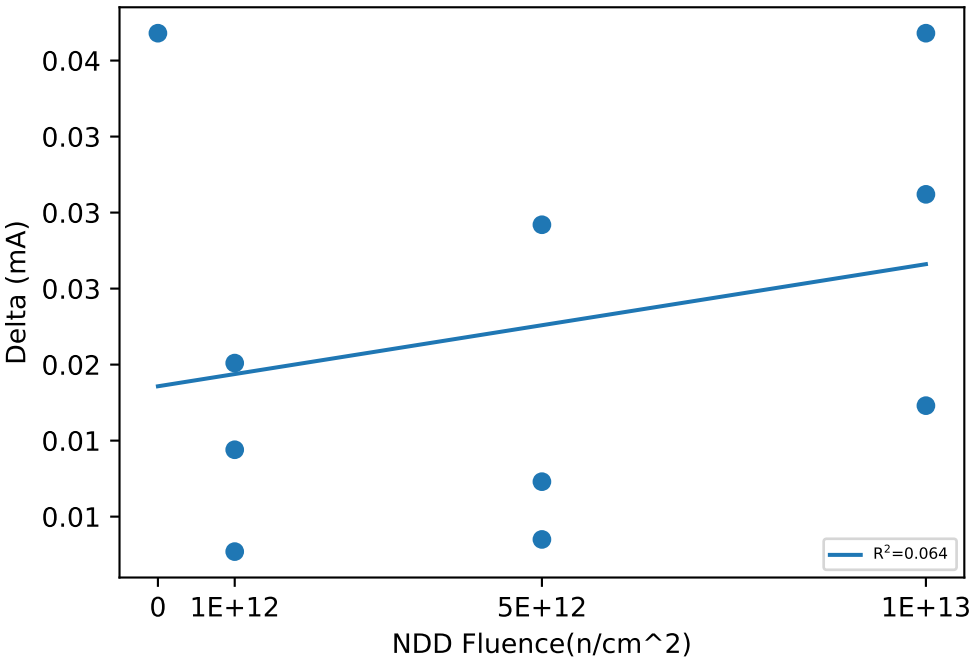
NDD vs Result Stats



Test Results (Upper Limit = 8.0 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	5.2794	5.2938	0.0144
551	1e+12	NDD	5.1388	5.1589	0.0201
552	1e+12	NDD	5.3067	5.3144	0.0077
553	5e+12	NDD	5.3294	5.3586	0.0292
554	5e+12	NDD	5.3574	5.3697	0.0123
555	5e+12	NDD	5.2947	5.3032	0.0085
556	1e+13	NDD	5.1461	5.1634	0.0173
557	1e+13	NDD	5.1695	5.2007	0.0312
558	1e+13	NDD	5.3852	5.427	0.0418
559	0	NDD, Ctrl	5.4	5.4418	0.0418

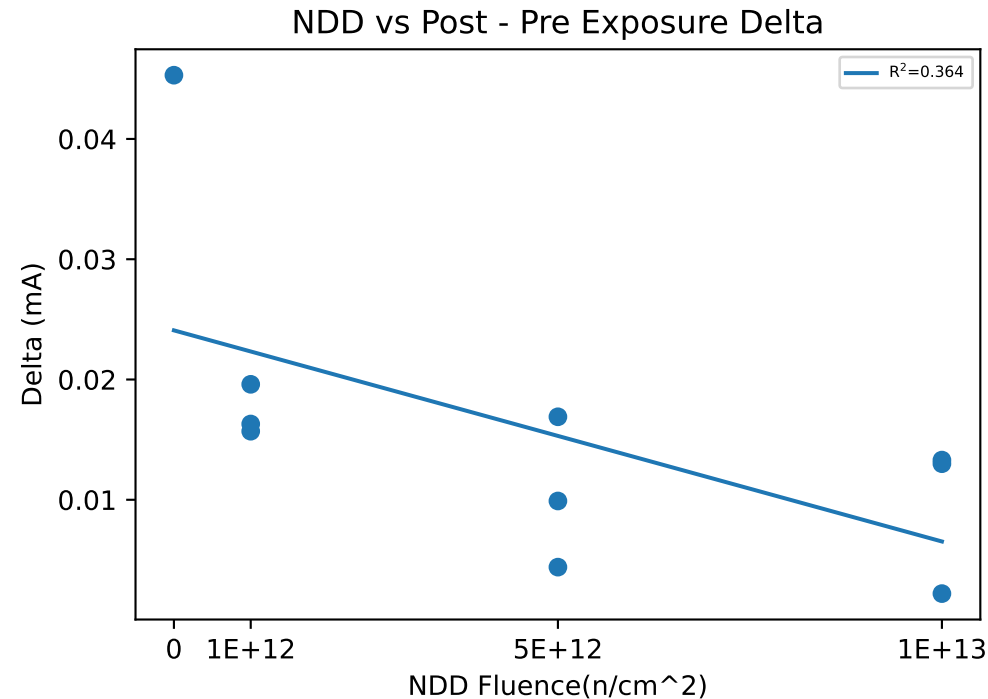
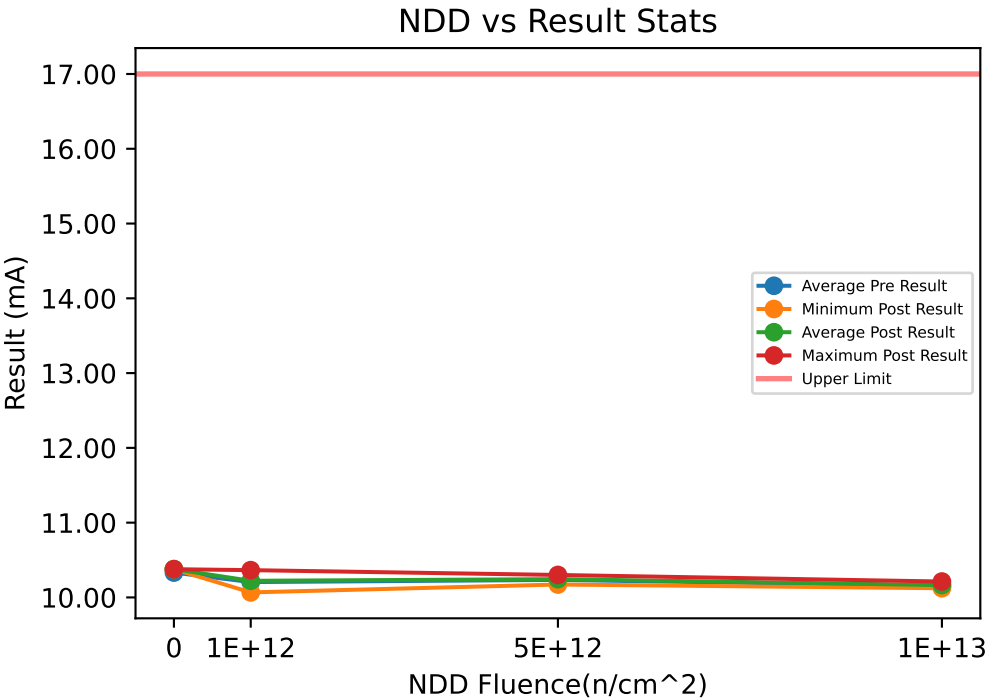
NDD vs Post - Pre Exposure Delta



Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.4	5.4	5.4		5.4418	5.4418	5.4418		0.0418	0.0418	0.0418	
1e+12	5.1388	5.2416	5.3067	0.090096	5.1589	5.2557	5.3144	0.084462	0.0077	0.014067	0.0201	0.0062067
5e+12	5.2947	5.3272	5.3574	0.03141	5.3032	5.3438	5.3697	0.035624	0.0085	0.016667	0.0292	0.011019
1e+13	5.1461	5.2336	5.3852	0.13181	5.1634	5.2637	5.427	0.14265	0.0173	0.0301	0.0418	0.012287

Device Test: 35.18 I_OP_LS_IIM_2MHZ_INTERLOCK(Iop LS VIN IIM Interlock 2MHz VIN_10V)



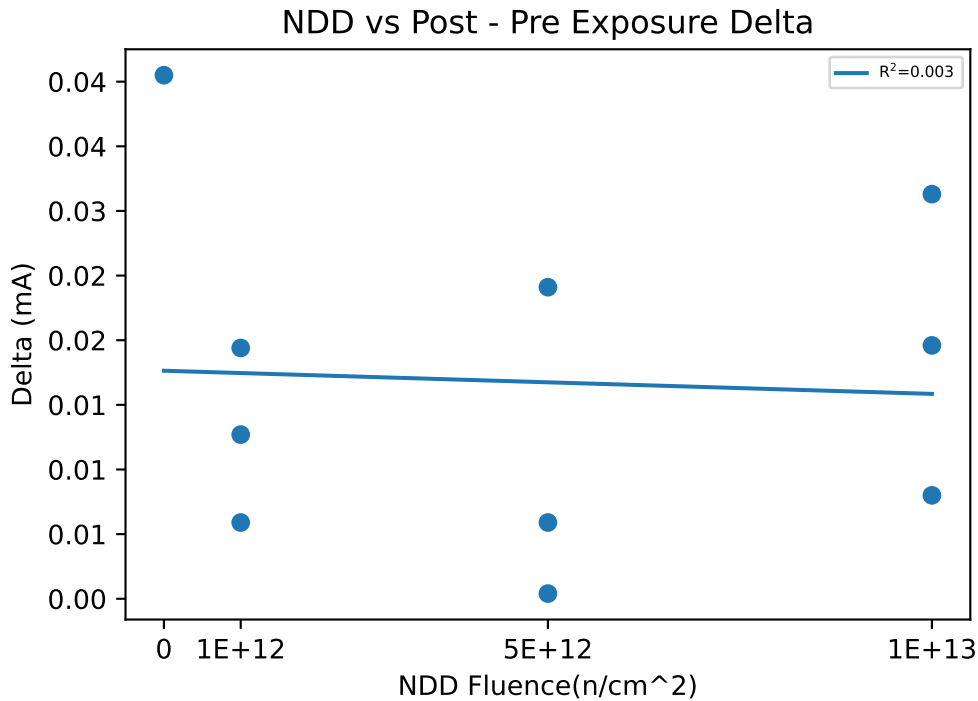
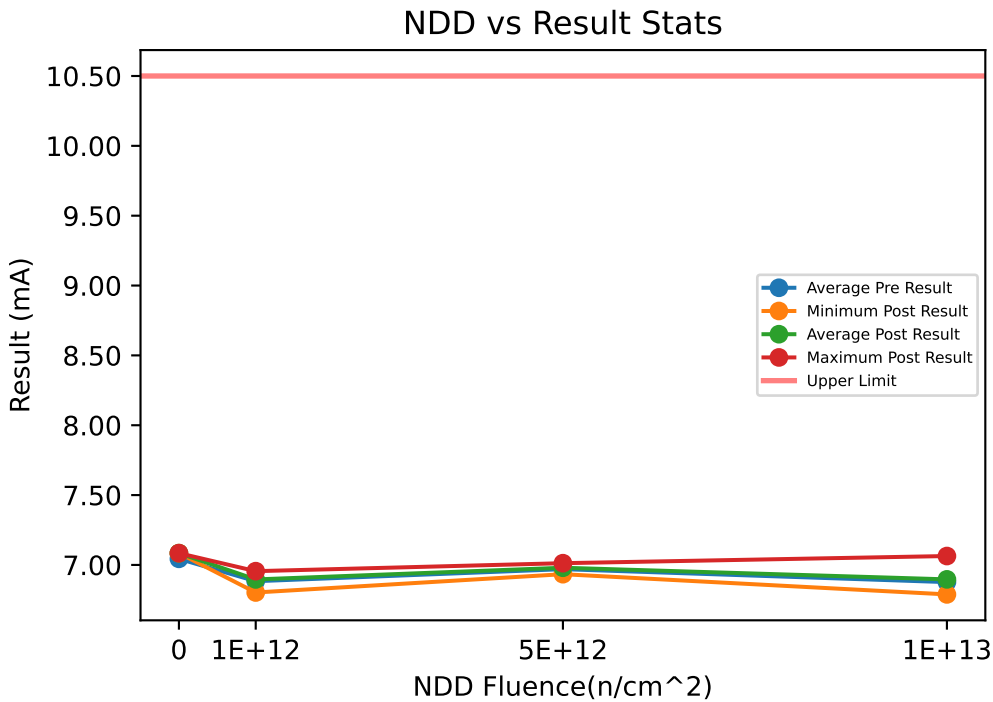
Test Results (Upper Limit = 17.0 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	10.219	10.235	0.0163
551	1e+12	NDD	10.052	10.067	0.0157
552	1e+12	NDD	10.345	10.365	0.0196
553	5e+12	NDD	10.243	10.26	0.0169
554	5e+12	NDD	10.296	10.3	0.0044
555	5e+12	NDD	10.163	10.173	0.0099
556	1e+13	NDD	10.11	10.123	0.013
557	1e+13	NDD	10.146	10.159	0.0133
558	1e+13	NDD	10.21	10.213	0.0022
559	0	NDD, Ctrl	10.332	10.378	0.0453

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	10.332	10.332	10.332		10.378	10.378	10.378		0.0453	0.0453	0.0453	
1e+12	10.052	10.205	10.345	0.14729	10.067	10.223	10.365	0.14917	0.0157	0.0172	0.0196	0.0021
5e+12	10.163	10.234	10.296	0.067128	10.173	10.244	10.3	0.065337	0.0044	0.0104	0.0169	0.006265
1e+13	10.11	10.155	10.21	0.050938	10.123	10.165	10.213	0.045134	0.0022	0.0095	0.0133	0.0063238

Device Test: 35.19 I_OP_HS_IIM_2MHZ_INTERLOCK(Iop HS BOOT IIM Interlock 2MHz VIN_10V)



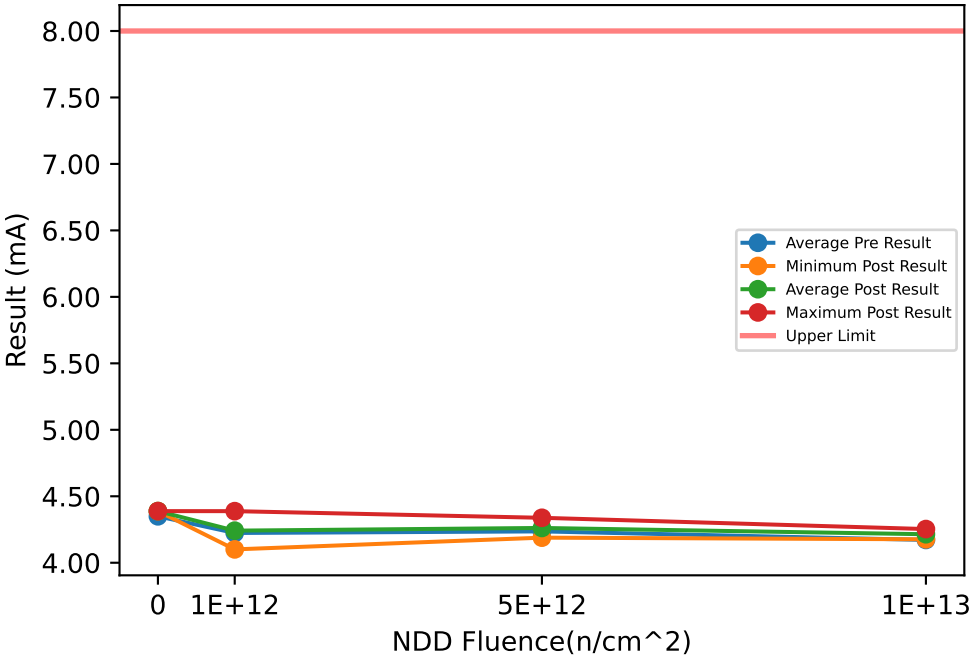
Test Results (Upper Limit = 10.5 (mA))					
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	6.9178	6.9305	0.0127
551	1e+12	NDD	6.7833	6.8027	0.0194
552	1e+12	NDD	6.9495	6.9554	0.0059
553	5e+12	NDD	6.9695	6.9936	0.0241
554	5e+12	NDD	7.0066	7.0125	0.0059
555	5e+12	NDD	6.9333	6.9337	0.0004
556	1e+13	NDD	6.7811	6.7891	0.008
557	1e+13	NDD	6.8177	6.8373	0.0196
558	1e+13	NDD	7.0324	7.0637	0.0313
559	0	NDD, Ctrl	7.0437	7.0842	0.0405

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0437	7.0437	7.0437		7.0842	7.0842	7.0842		0.0405	0.0405	0.0405	
1e+12	6.7833	6.8835	6.9495	0.08824	6.8027	6.8962	6.9554	0.081925	0.0059	0.012667	0.0194	0.0067501
5e+12	6.9333	6.9698	7.0066	0.036651	6.9337	6.9799	7.0125	0.041139	0.0004	0.010133	0.0241	0.012404
1e+13	6.7811	6.8771	7.0324	0.13576	6.7891	6.8967	7.0637	0.14662	0.008	0.019633	0.0313	0.01165

Device Test: 35.2 IQ_LS_IIM_INTERLOCK(Iq LS VIN IIM Interlock VIN_10V)

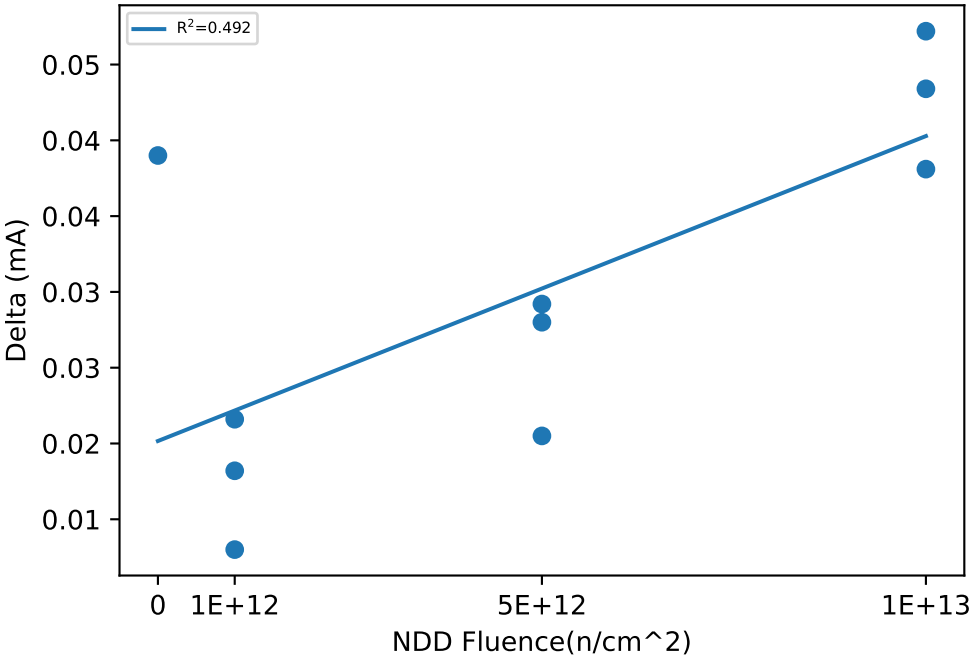
NDD vs Result Stats



Test Results (Upper Limit = 8.0 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.2178	4.236	0.0182
551	1e+12	NDD	4.0874	4.1004	0.013
552	1e+12	NDD	4.3665	4.3881	0.0216
553	5e+12	NDD	4.2304	4.2584	0.028
554	5e+12	NDD	4.3176	4.3381	0.0205
555	5e+12	NDD	4.1595	4.1887	0.0292
556	1e+13	NDD	4.1663	4.2135	0.0472
557	1e+13	NDD	4.133	4.1764	0.0434
558	1e+13	NDD	4.2153	4.2534	0.0381
559	0	NDD, Ctrl	4.3493	4.3883	0.039

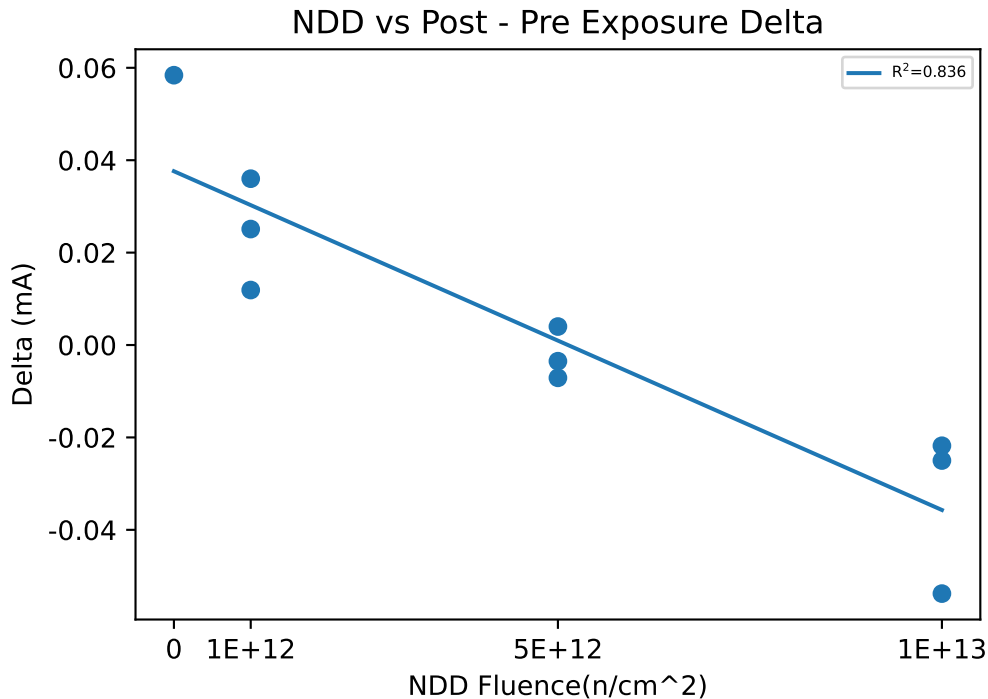
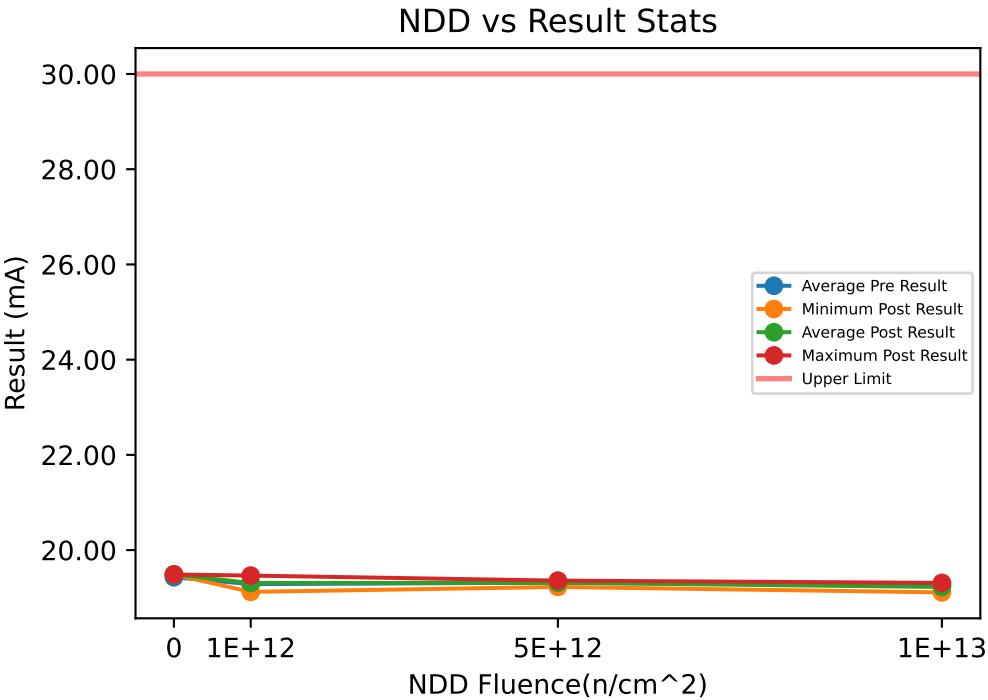
NDD vs Post - Pre Exposure Delta



Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.3493	4.3493	4.3493		4.3883	4.3883	4.3883		0.039	0.039	0.039	
1e+12	4.0874	4.2239	4.3665	0.13965	4.1004	4.2415	4.3881	0.14393	0.013	0.0176	0.0216	0.0043313
5e+12	4.1595	4.2358	4.3176	0.07919	4.1887	4.2617	4.3381	0.074756	0.0205	0.0259	0.0292	0.0047149
1e+13	4.133	4.1715	4.2153	0.041399	4.1764	4.2144	4.2534	0.038508	0.0381	0.0429	0.0472	0.0045706

Device Test: 35.20 I_OP_LS_IIM_5MHZ_INTERLOCK(Iop LS VIN IIM Interlock 5MHz VIN_10V)

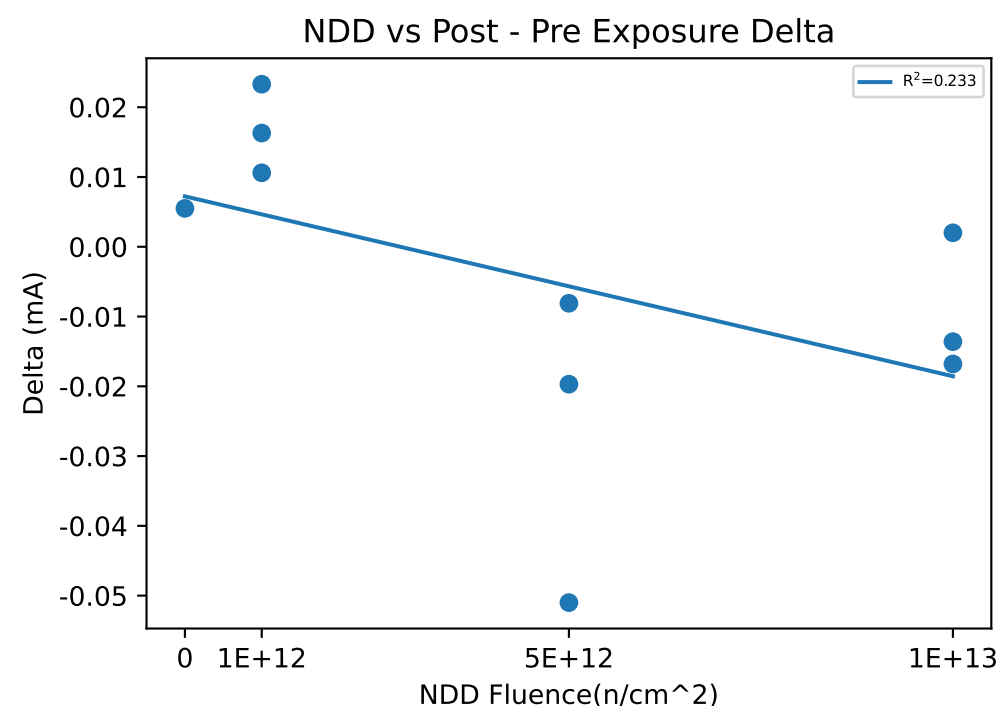
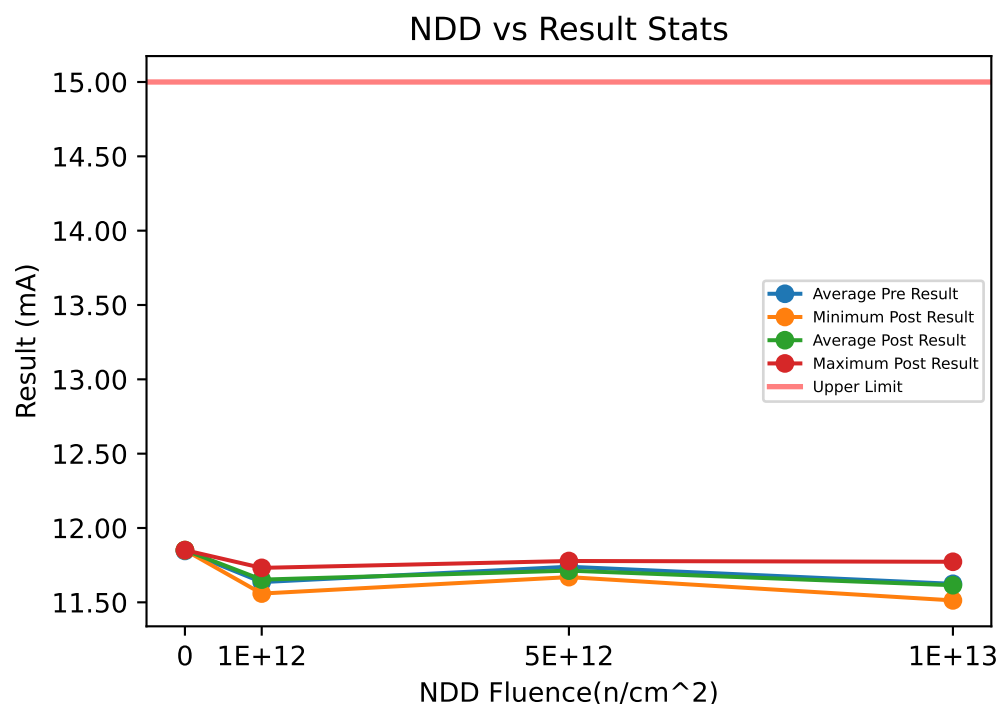


Test Results (Upper Limit = 30.0 (mA))					
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	19.316	19.341	0.0251
551	1e+12	NDD	19.11	19.122	0.0119
552	1e+12	NDD	19.429	19.465	0.036
553	5e+12	NDD	19.362	19.355	-0.0071
554	5e+12	NDD	19.362	19.359	-0.0035
555	5e+12	NDD	19.222	19.226	0.004
556	1e+13	NDD	19.133	19.111	-0.0218
557	1e+13	NDD	19.279	19.254	-0.025
558	1e+13	NDD	19.365	19.311	-0.0538
559	0	NDD, Ctrl	19.43	19.488	0.0584

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	19.43	19.43	19.43		19.488	19.488	19.488		0.0584	0.0584	0.0584	
1e+12	19.11	19.285	19.429	0.1613	19.122	19.309	19.465	0.17329	0.0119	0.024333	0.036	0.012068
5e+12	19.222	19.316	19.362	0.080829	19.226	19.313	19.359	0.075479	-0.0071	-0.0022	0.004	0.005663
1e+13	19.133	19.259	19.365	0.11717	19.111	19.226	19.311	0.10291	-0.0538	-0.033533	-0.0218	0.017624

Device Test: 35.21 I_OP_HS_IIM_5MHZ_INTERLOCK(Iop HS BOOT IIM Interlock 5MHz VIN_10V)



Test Results (Upper Limit = 15.0 (mA))

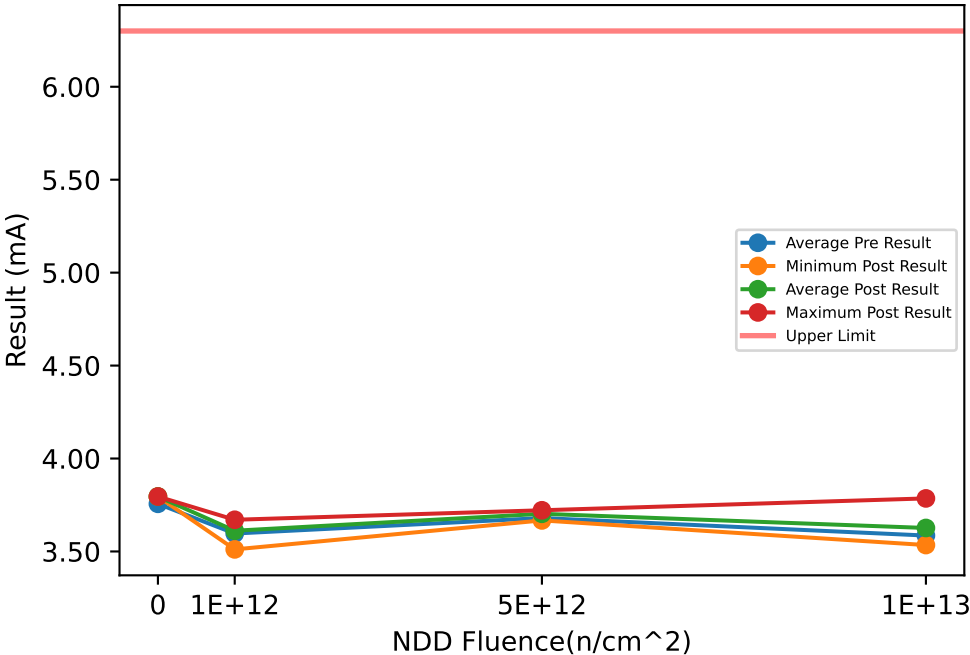
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	11.657	11.668	0.0106
551	1e+12	NDD	11.536	11.559	0.0233
552	1e+12	NDD	11.716	11.732	0.0163
553	5e+12	NDD	11.7	11.692	-0.0081
554	5e+12	NDD	11.798	11.778	-0.0197
555	5e+12	NDD	11.72	11.669	-0.051
556	1e+13	NDD	11.53	11.513	-0.0168
557	1e+13	NDD	11.573	11.559	-0.0136
558	1e+13	NDD	11.771	11.773	0.002
559	0	NDD, Ctrl	11.846	11.851	0.0055

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	11.846	11.846	11.846		11.851	11.851	11.851		0.0055	0.0055	0.0055	
1e+12	11.536	11.636	11.716	0.091698	11.559	11.653	11.732	0.087337	0.0106	0.016733	0.0233	0.0063611
5e+12	11.7	11.739	11.798	0.051443	11.669	11.713	11.778	0.057245	-0.051	-0.026267	-0.0081	0.022191
1e+13	11.53	11.625	11.771	0.12848	11.513	11.615	11.773	0.13854	-0.0168	-0.0094667	0.002	0.010058

Device Test: 35.3 IQ_HS_IIM_INTERLOCK(Iq HS BOOT IIM Interlock VIN_10V)

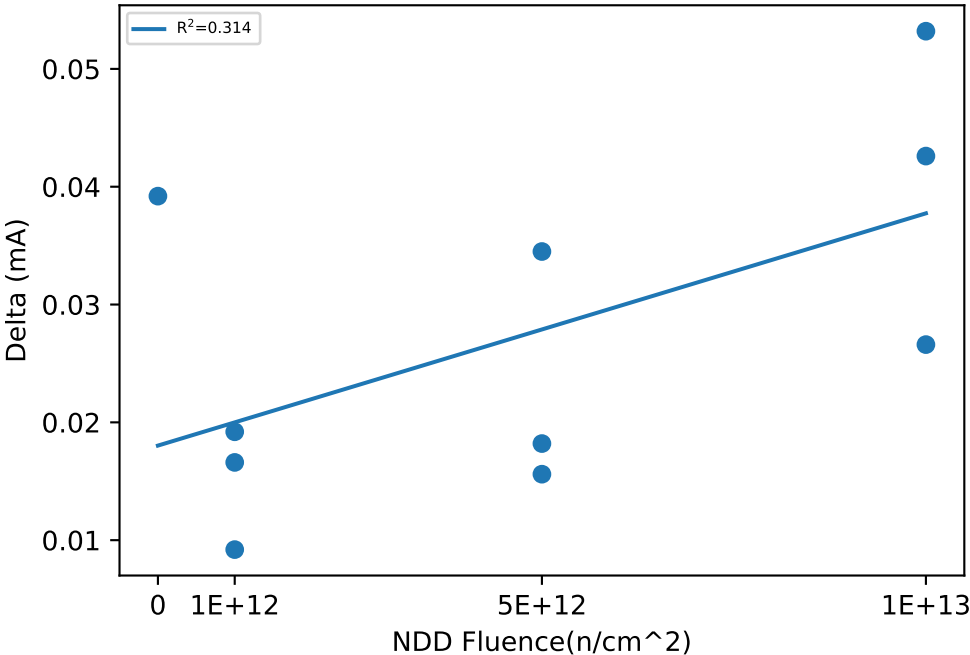
NDD vs Result Stats



Test Results (Upper Limit = 6.3 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	3.6363	3.6529	0.0166
551	1e+12	NDD	3.4919	3.5111	0.0192
552	1e+12	NDD	3.6613	3.6705	0.0092
553	5e+12	NDD	3.6846	3.7191	0.0345
554	5e+12	NDD	3.7034	3.7216	0.0182
555	5e+12	NDD	3.6514	3.667	0.0156
556	1e+13	NDD	3.5079	3.5345	0.0266
557	1e+13	NDD	3.5167	3.5593	0.0426
558	1e+13	NDD	3.7322	3.7854	0.0532
559	0	NDD, Ctrl	3.7563	3.7955	0.0392

NDD vs Post - Pre Exposure Delta

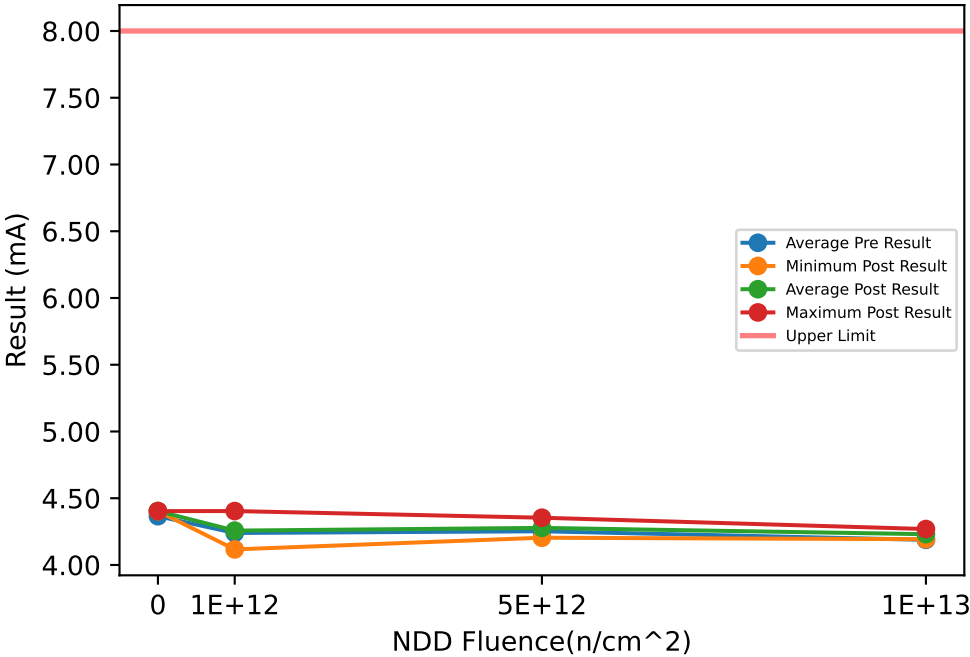


Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7563	3.7563	3.7563		3.7955	3.7955	3.7955		0.0392	0.0392	0.0392	
1e+12	3.4919	3.5965	3.6613	0.091445	3.5111	3.6115	3.6705	0.087393	0.0092	0.015	0.0192	0.0051884
5e+12	3.6514	3.6798	3.7034	0.02633	3.667	3.7026	3.7216	0.030827	0.0156	0.022767	0.0345	0.010244
1e+13	3.5079	3.5856	3.7322	0.12704	3.5345	3.6264	3.7854	0.13826	0.0266	0.0408	0.0532	0.013391

Device Test: 35.4 IQ_LS_IIM_INTERLOCK_DIS(Iq LS VIN IIM Interlock Disable VIN_10V)

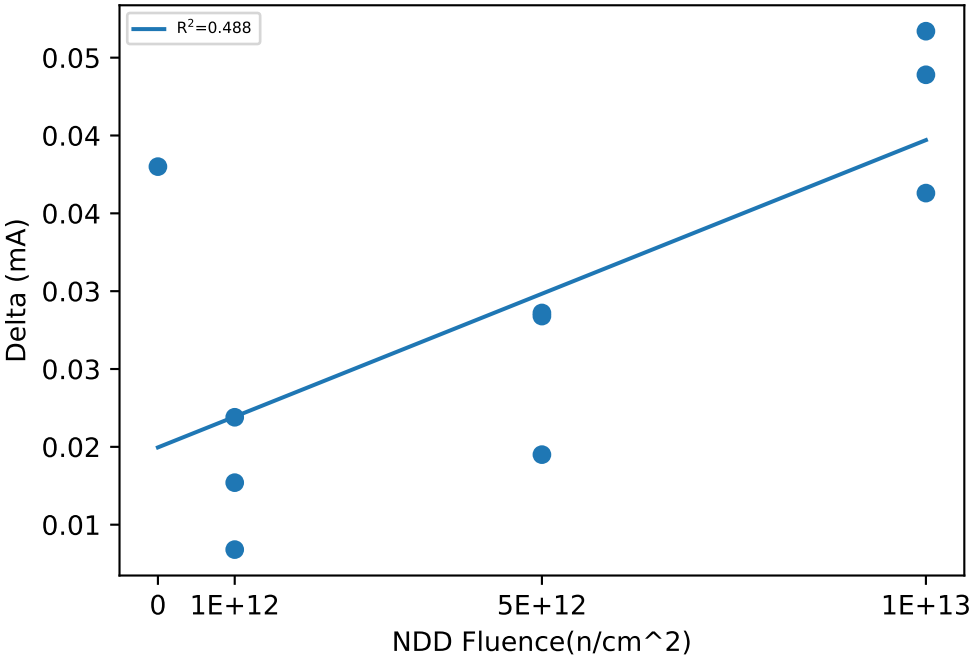
NDD vs Result Stats



Test Results (Upper Limit = 8.0 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.2341	4.2518	0.0177
551	1e+12	NDD	4.1033	4.1167	0.0134
552	1e+12	NDD	4.382	4.4039	0.0219
553	5e+12	NDD	4.2473	4.2757	0.0284
554	5e+12	NDD	4.3345	4.354	0.0195
555	5e+12	NDD	4.1755	4.2041	0.0286
556	1e+13	NDD	4.1828	4.2295	0.0467
557	1e+13	NDD	4.1491	4.193	0.0439
558	1e+13	NDD	4.2329	4.2692	0.0363
559	0	NDD, Ctrl	4.3655	4.4035	0.038

NDD vs Post - Pre Exposure Delta

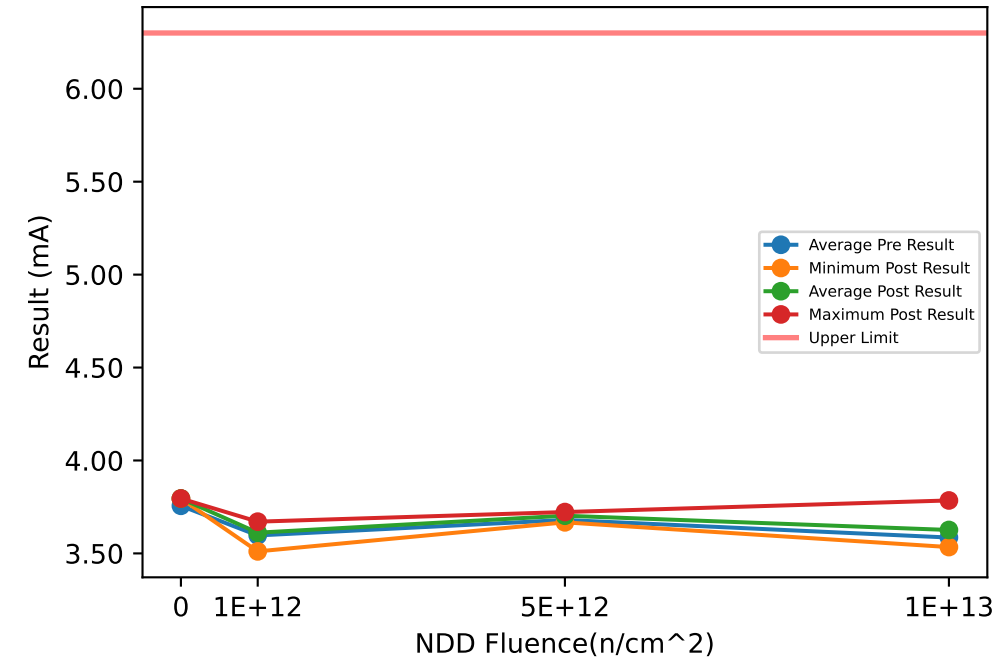


Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.3655	4.3655	4.3655		4.4035	4.4035	4.4035		0.038	0.038	0.038	
1e+12	4.1033	4.2398	4.382	0.13944	4.1167	4.2575	4.4039	0.14368	0.0134	0.017667	0.0219	0.0042501
5e+12	4.1755	4.2524	4.3345	0.079624	4.2041	4.2779	4.354	0.074975	0.0195	0.0255	0.0286	0.0051971
1e+13	4.1491	4.1883	4.2329	0.042167	4.193	4.2306	4.2692	0.038111	0.0363	0.0423	0.0467	0.0053814

Device Test: 35.5 IQ_HS_IIM_INTERLOCK_DIS(Iq HS BOOT IIM Interlock Disable VIN_10V)

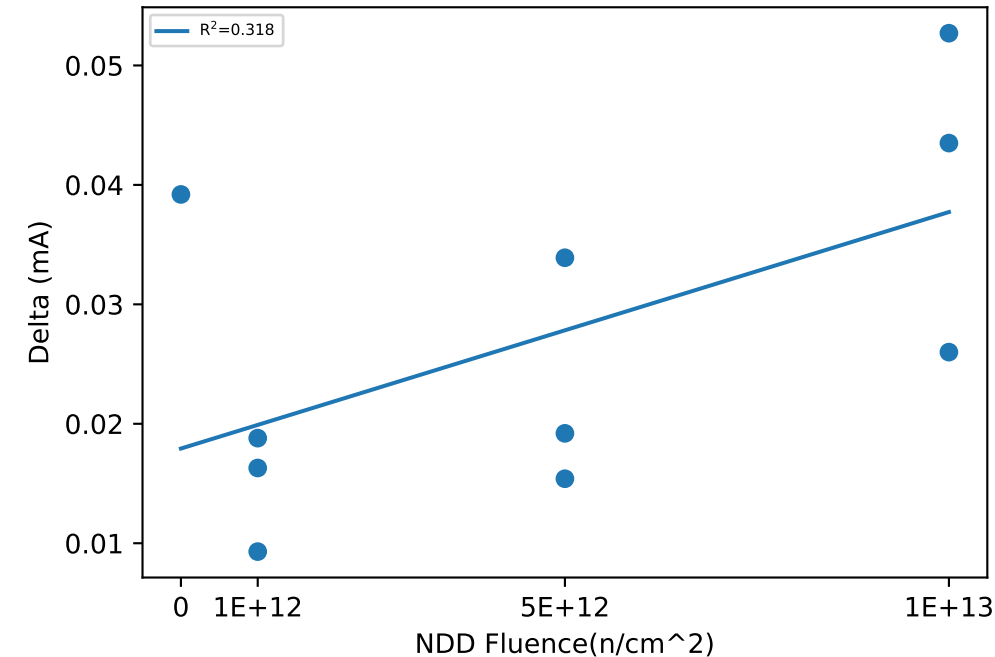
NDD vs Result Stats



Test Results (Upper Limit = 6.3 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	3.6365	3.6528	0.0163
551	1e+12	NDD	3.492	3.5108	0.0188
552	1e+12	NDD	3.6615	3.6708	0.0093
553	5e+12	NDD	3.6849	3.7188	0.0339
554	5e+12	NDD	3.7033	3.7225	0.0192
555	5e+12	NDD	3.6517	3.6671	0.0154
556	1e+13	NDD	3.5081	3.5341	0.026
557	1e+13	NDD	3.5159	3.5594	0.0435
558	1e+13	NDD	3.7322	3.7849	0.0527
559	0	NDD, Ctrl	3.7561	3.7953	0.0392

NDD vs Post - Pre Exposure Delta

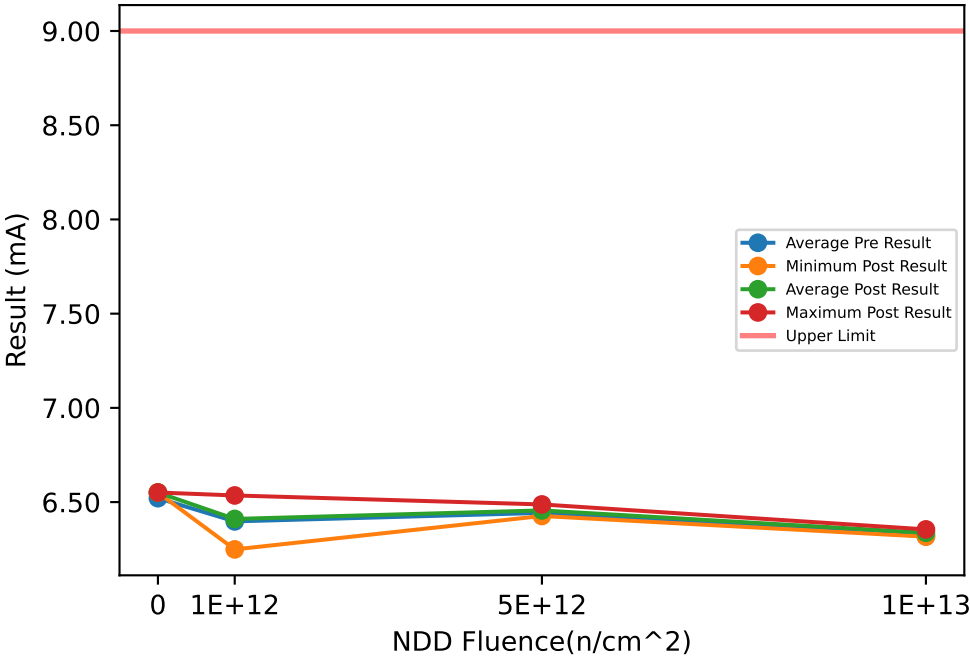


Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7561	3.7561	3.7561		3.7953	3.7953	3.7953		0.0392	0.0392	0.0392	
1e+12	3.492	3.5967	3.6615	0.091502	3.5108	3.6115	3.6708	0.087643	0.0093	0.0148	0.0188	0.0049244
5e+12	3.6517	3.68	3.7033	0.026151	3.6671	3.7028	3.7225	0.030972	0.0154	0.022833	0.0339	0.0097705
1e+13	3.5081	3.5854	3.7322	0.12719	3.5341	3.6261	3.7849	0.13808	0.026	0.040733	0.0527	0.013563

Device Test: 35.6 I_OP_LS_PWM_500KHZ(Iop LS VIN PWM 500kHz VIN_10V)

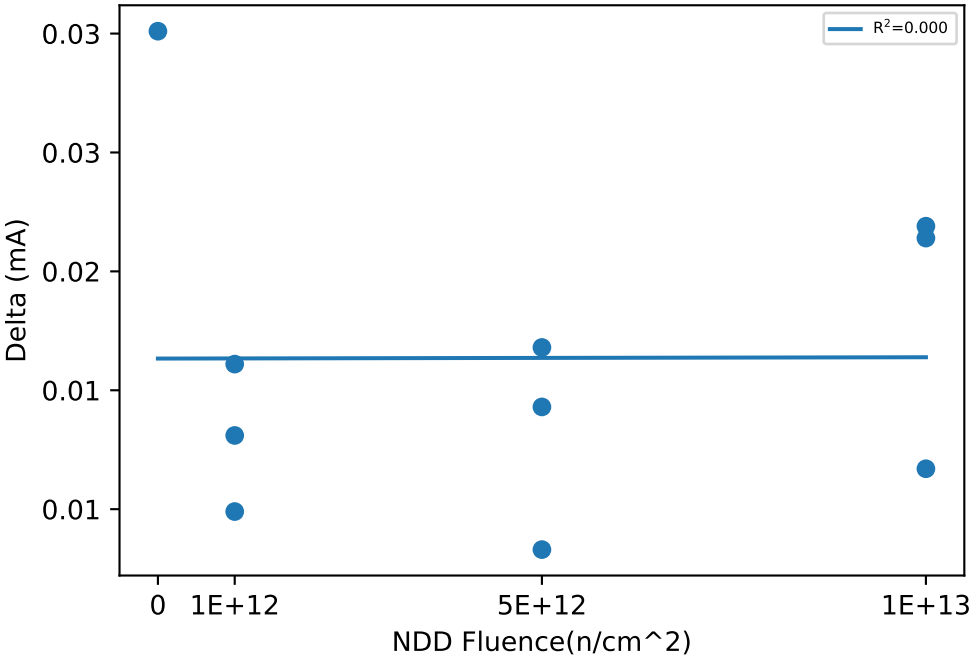
NDD vs Result Stats



Test Results (Upper Limit = 9.0 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	6.4346	6.4477	0.0131
551	1e+12	NDD	6.2391	6.249	0.0099
552	1e+12	NDD	6.5192	6.5353	0.0161
553	5e+12	NDD	6.4394	6.4537	0.0143
554	5e+12	NDD	6.4793	6.4876	0.0083
555	5e+12	NDD	6.4095	6.4263	0.0168
556	1e+13	NDD	6.3176	6.3395	0.0219
557	1e+13	NDD	6.3338	6.3552	0.0214
558	1e+13	NDD	6.3049	6.3166	0.0117
559	0	NDD, Ctrl	6.5208	6.5509	0.0301

NDD vs Post - Pre Exposure Delta

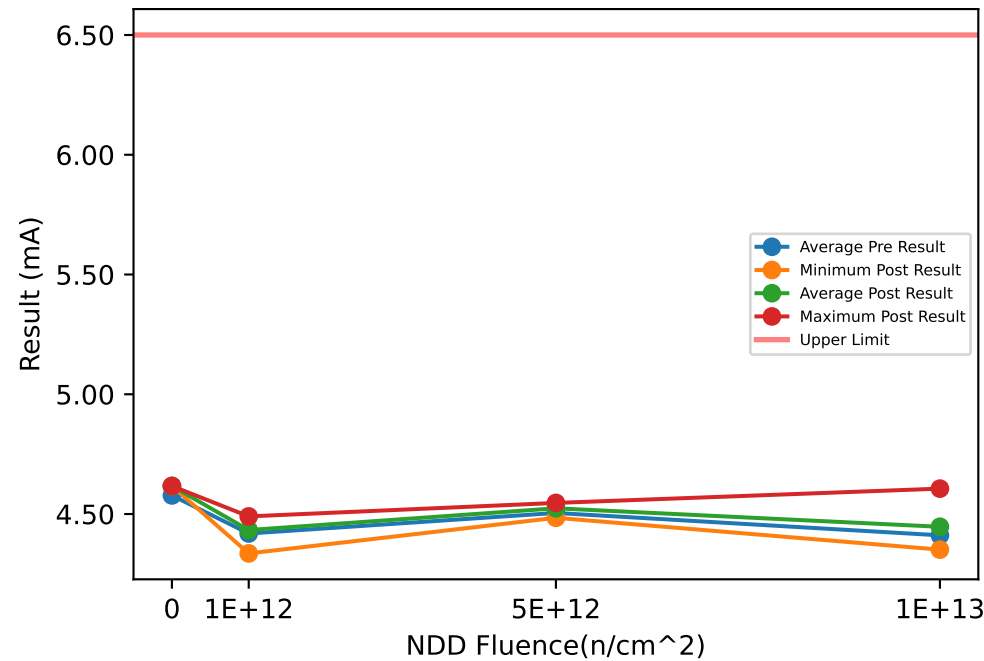


Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.5208	6.5208	6.5208		6.5509	6.5509	6.5509		0.0301	0.0301	0.0301	
1e+12	6.2391	6.3976	6.5192	0.14366	6.249	6.4107	6.5353	0.1467	0.0099	0.013033	0.0161	0.0031005
5e+12	6.4095	6.4427	6.4793	0.035019	6.4263	6.4559	6.4876	0.030707	0.0083	0.013133	0.0168	0.0043684
1e+13	6.3049	6.3188	6.3338	0.014485	6.3166	6.3371	6.3552	0.019412	0.0117	0.018333	0.0219	0.0057501

Device Test: 35.7 I_OP_HS_PWM_500KHZ(lop HS BOOT PWM 500kHz VIN_10V)

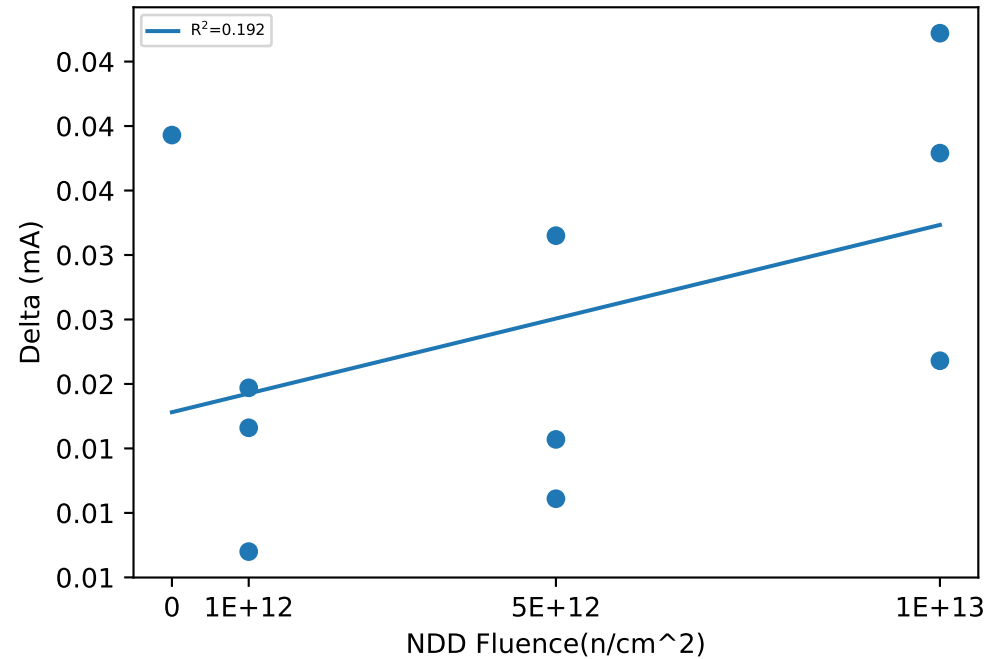
NDD vs Result Stats



Test Results (Upper Limit = 6.5 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.4571	4.4737	0.0166
551	1e+12	NDD	4.3159	4.3356	0.0197
552	1e+12	NDD	4.4831	4.4901	0.007
553	5e+12	NDD	4.5096	4.5411	0.0315
554	5e+12	NDD	4.5306	4.5463	0.0157
555	5e+12	NDD	4.4732	4.4843	0.0111
556	1e+13	NDD	4.3295	4.3513	0.0218
557	1e+13	NDD	4.345	4.3829	0.0379
558	1e+13	NDD	4.5588	4.606	0.0472
559	0	NDD, Ctrl	4.5776	4.6169	0.0393

NDD vs Post - Pre Exposure Delta

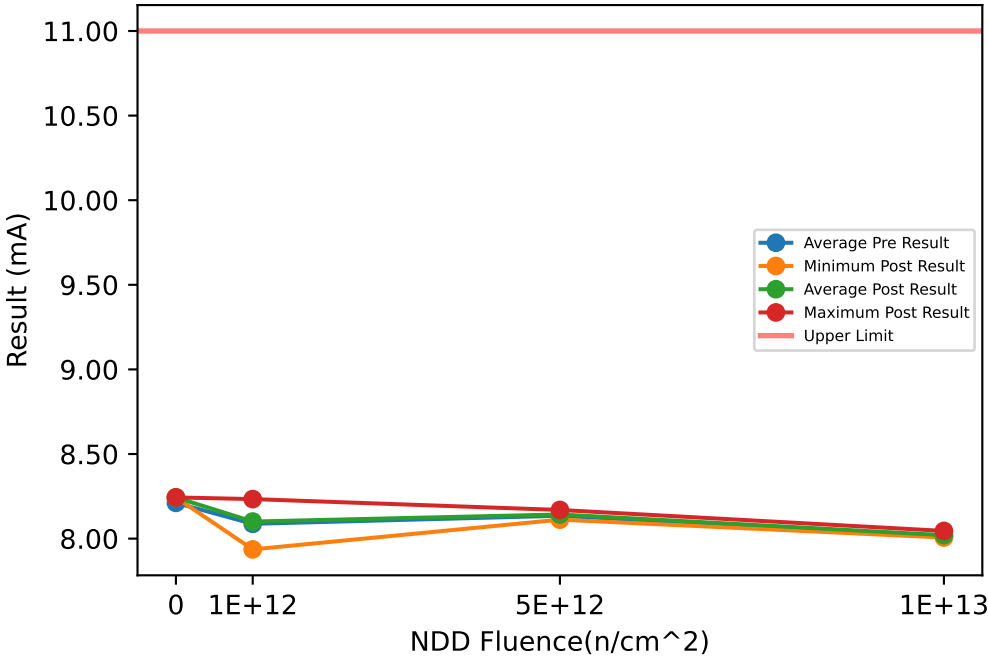


Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.5776	4.5776	4.5776		4.6169	4.6169	4.6169		0.0393	0.0393	0.0393	
1e+12	4.3159	4.4187	4.4831	0.089972	4.3356	4.4331	4.4901	0.084863	0.007	0.014433	0.0197	0.0066214
5e+12	4.4732	4.5045	4.5306	0.029042	4.4843	4.5239	4.5463	0.034393	0.0111	0.019433	0.0315	0.0107
1e+13	4.3295	4.4111	4.5588	0.12815	4.3513	4.4467	4.606	0.13883	0.0218	0.035633	0.0472	0.012851

Device Test: 35.8 I_OP_LS_PWM_1MHZ(Iop LS VIN PWM 1MHz VIN_10V)

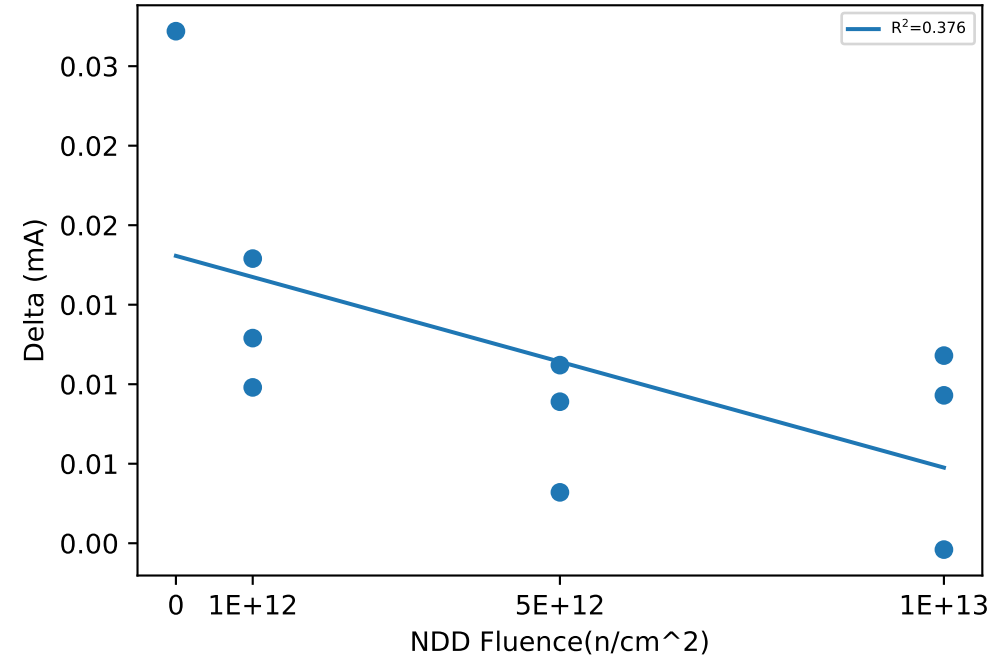
NDD vs Result Stats



Test Results (Upper Limit = 11.0 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	8.1199	8.1328	0.0129
551	1e+12	NDD	7.9265	7.9363	0.0098
552	1e+12	NDD	8.2157	8.2336	0.0179
553	5e+12	NDD	8.1356	8.1468	0.0112
554	5e+12	NDD	8.1662	8.1694	0.0032
555	5e+12	NDD	8.1032	8.1121	0.0089
556	1e+13	NDD	7.9978	8.0096	0.0118
557	1e+13	NDD	8.0362	8.0455	0.0093
558	1e+13	NDD	8.0067	8.0063	-0.0004
559	0	NDD, Ctrl	8.2112	8.2434	0.0322

NDD vs Post - Pre Exposure Delta

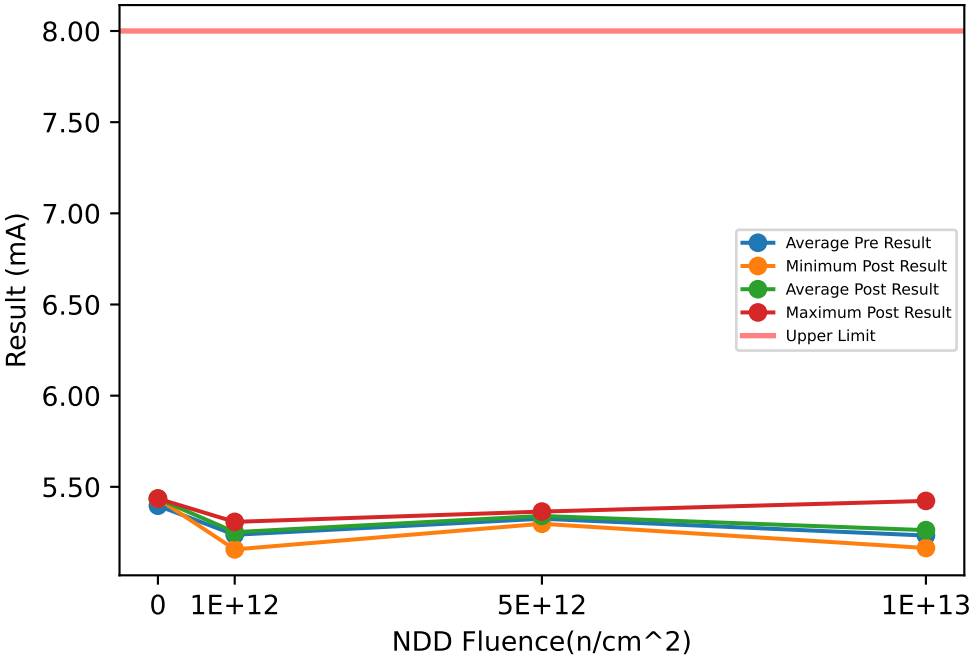


Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.2112	8.2112	8.2112		8.2434	8.2434	8.2434		0.0322	0.0322	0.0322	
1e+12	7.9265	8.0874	8.2157	0.14732	7.9363	8.1009	8.2336	0.1512	0.0098	0.013533	0.0179	0.004087
5e+12	8.1032	8.135	8.1662	0.031504	8.1121	8.1428	8.1694	0.028862	0.0032	0.0077667	0.0112	0.0041187
1e+13	7.9978	8.0136	8.0362	0.0201	8.0063	8.0205	8.0455	0.021742	-0.0004	0.0069	0.0118	0.0064444

Device Test: 35.9 I_OP_HS_PWM_1MHZ(lop HS BOOT PWM 1MHz VIN_10V)

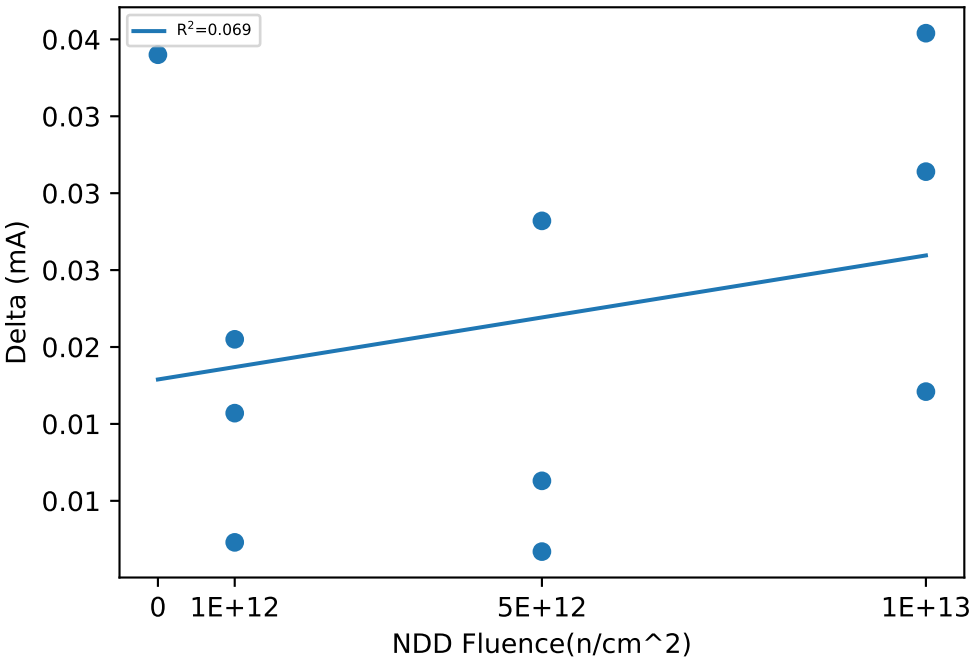
NDD vs Result Stats



Test Results (Upper Limit = 8.0 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	5.2741	5.2898	0.0157
551	1e+12	NDD	5.1364	5.1569	0.0205
552	1e+12	NDD	5.3006	5.3079	0.0073
553	5e+12	NDD	5.3313	5.3595	0.0282
554	5e+12	NDD	5.353	5.3643	0.0113
555	5e+12	NDD	5.2907	5.2974	0.0067
556	1e+13	NDD	5.1473	5.1644	0.0171
557	1e+13	NDD	5.1689	5.2003	0.0314
558	1e+13	NDD	5.3824	5.4228	0.0404
559	0	NDD, Ctrl	5.3965	5.4355	0.039

NDD vs Post - Pre Exposure Delta

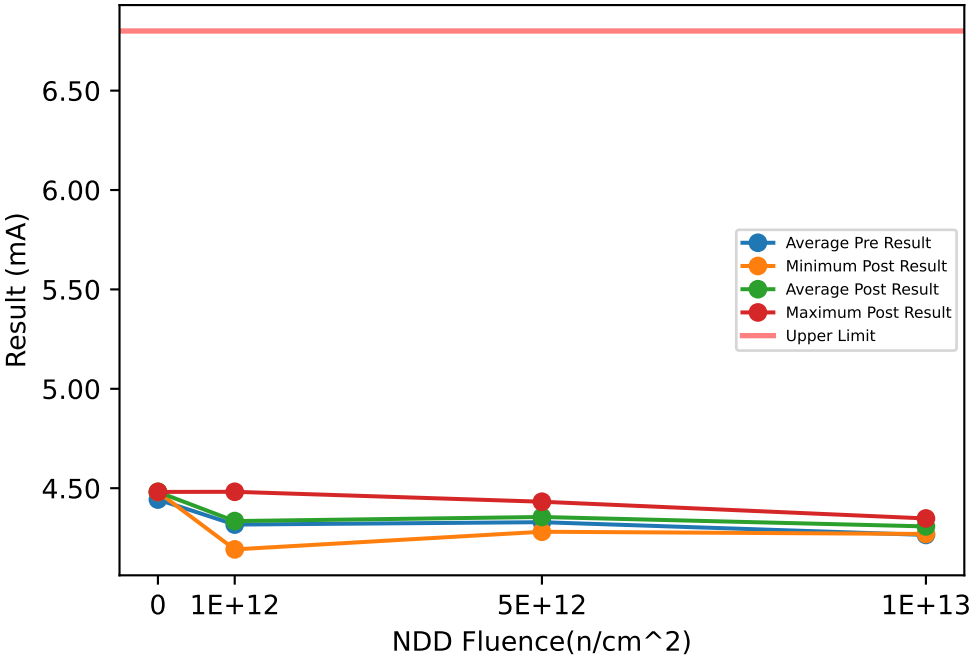


Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.3965	5.3965	5.3965		5.4355	5.4355	5.4355		0.039	0.039	0.039	
1e+12	5.1364	5.237	5.3006	0.088153	5.1569	5.2515	5.3079	0.082453	0.0073	0.0145	0.0205	0.0066813
5e+12	5.2907	5.325	5.353	0.031624	5.2974	5.3404	5.3643	0.037316	0.0067	0.0154	0.0282	0.011321
1e+13	5.1473	5.2329	5.3824	0.12995	5.1644	5.2625	5.4228	0.13998	0.0171	0.029633	0.0404	0.01175

Device Test: 36.0 IQ_LS_PWM(Iq LS VIN PWM VIN_12V)

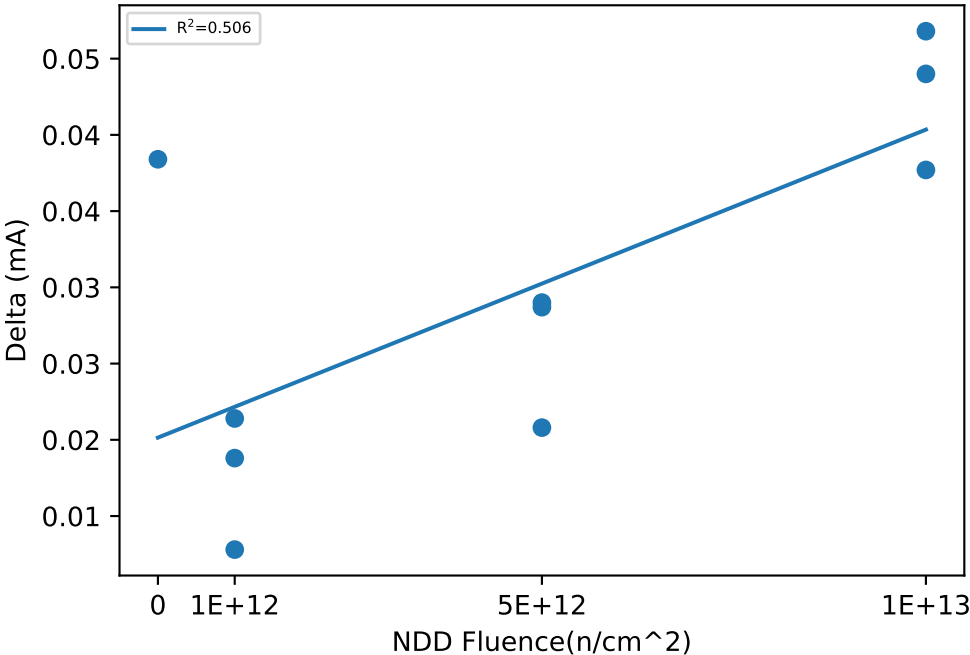
NDD vs Result Stats



Test Results (Upper Limit = 6.8 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.311	4.3298	0.0188
551	1e+12	NDD	4.1793	4.1921	0.0128
552	1e+12	NDD	4.4605	4.4819	0.0214
553	5e+12	NDD	4.324	4.3527	0.0287
554	5e+12	NDD	4.4111	4.4319	0.0208
555	5e+12	NDD	4.2519	4.2809	0.029
556	1e+13	NDD	4.2587	4.3055	0.0468
557	1e+13	NDD	4.2258	4.2698	0.044
558	1e+13	NDD	4.3101	4.3478	0.0377
559	0	NDD, Ctrl	4.4428	4.4812	0.0384

NDD vs Post - Pre Exposure Delta

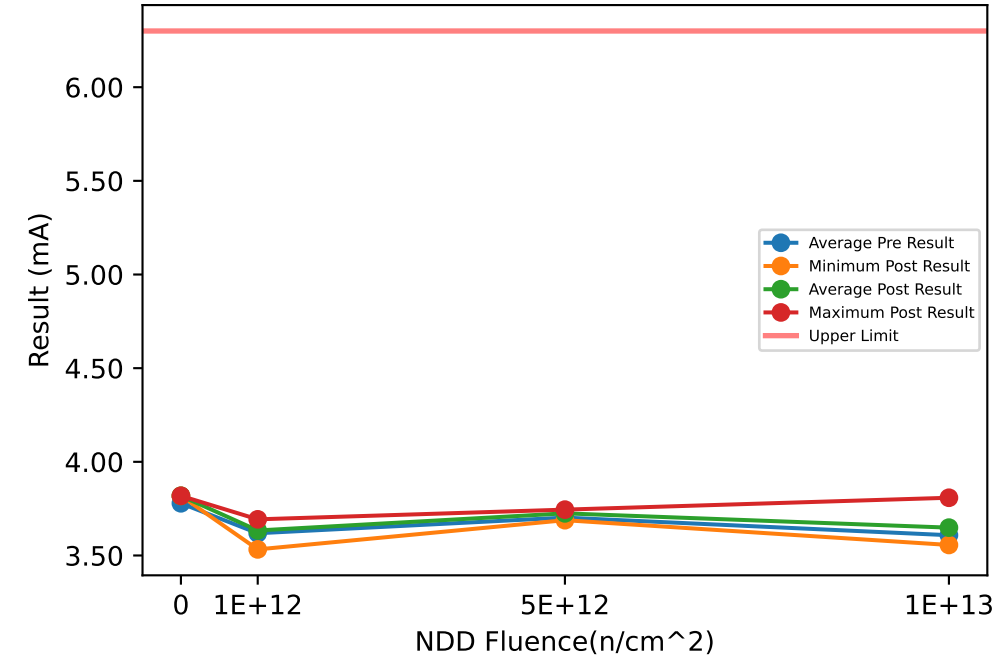


Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.4428	4.4428	4.4428		4.4812	4.4812	4.4812		0.0384	0.0384	0.0384	
1e+12	4.1793	4.3169	4.4605	0.14069	4.1921	4.3346	4.4819	0.14496	0.0128	0.017667	0.0214	0.0044106
5e+12	4.2519	4.329	4.4111	0.079718	4.2809	4.3552	4.4319	0.07553	0.0208	0.026167	0.029	0.0046501
1e+13	4.2258	4.2649	4.3101	0.042487	4.2698	4.3077	4.3478	0.039047	0.0377	0.042833	0.0468	0.0046608

Device Test: 36.1 IQ_HS_PWM(Iq HS BOOT PWM VIN_12V)

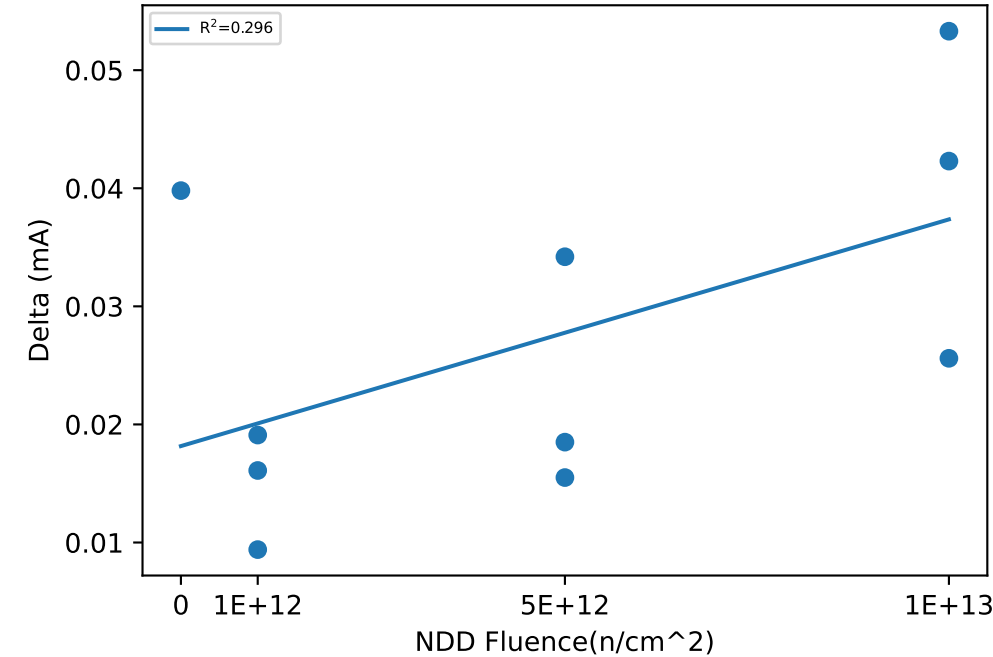
NDD vs Result Stats



Test Results (Upper Limit = 6.3 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	3.6591	3.6752	0.0161
551	1e+12	NDD	3.5134	3.5325	0.0191
552	1e+12	NDD	3.6836	3.693	0.0094
553	5e+12	NDD	3.7074	3.7416	0.0342
554	5e+12	NDD	3.7263	3.7448	0.0185
555	5e+12	NDD	3.6729	3.6884	0.0155
556	1e+13	NDD	3.5306	3.5562	0.0256
557	1e+13	NDD	3.5393	3.5816	0.0423
558	1e+13	NDD	3.7549	3.8082	0.0533
559	0	NDD, Ctrl	3.7786	3.8184	0.0398

NDD vs Post - Pre Exposure Delta

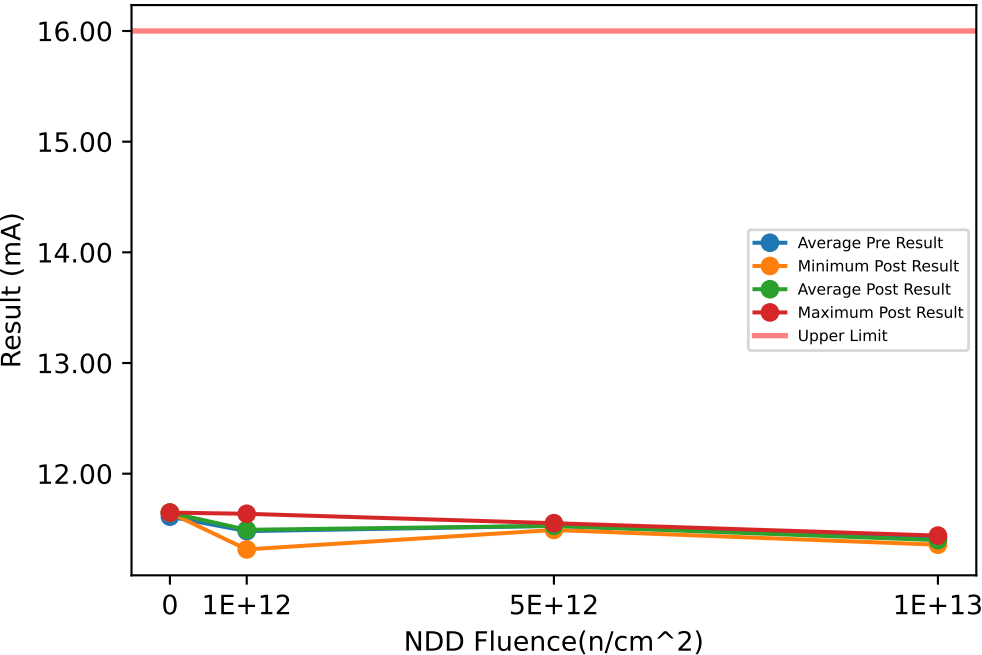


Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7786	3.7786	3.7786		3.8184	3.8184	3.8184		0.0398	0.0398	0.0398	
1e+12	3.5134	3.6187	3.6836	0.092012	3.5325	3.6336	3.693	0.087978	0.0094	0.014867	0.0191	0.0049662
5e+12	3.6729	3.7022	3.7263	0.027077	3.6884	3.7249	3.7448	0.031679	0.0155	0.022733	0.0342	0.010043
1e+13	3.5306	3.6083	3.7549	0.12706	3.5562	3.6487	3.8082	0.13874	0.0256	0.0404	0.0533	0.013947

Device Test: 36.10 I_OP_LS_PWM_2MHZ(lop LS VIN PWM 2MHz VIN_12V)

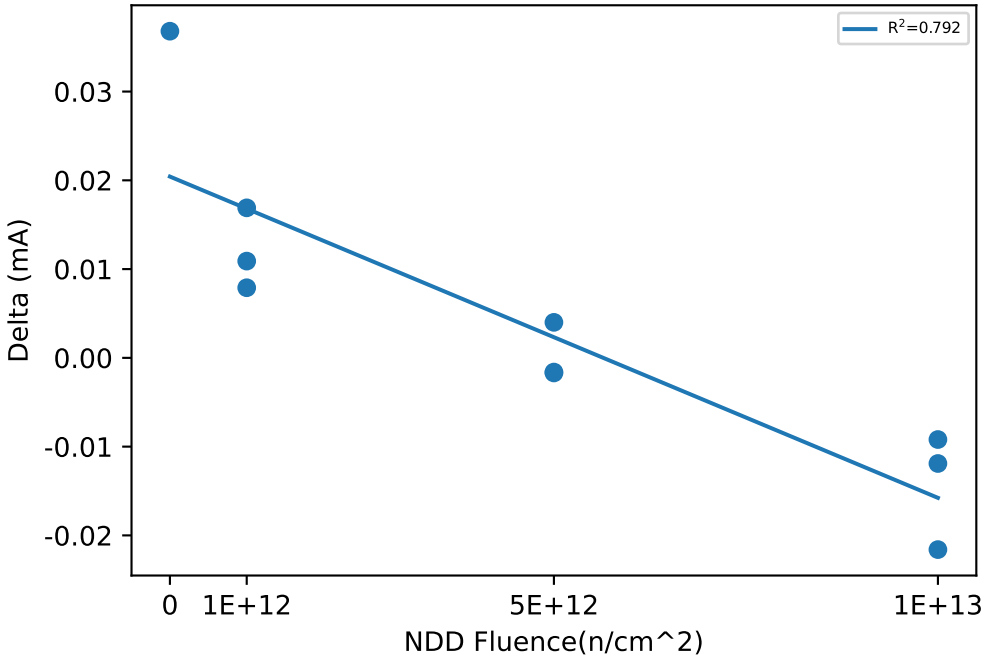
NDD vs Result Stats



Test Results (Upper Limit = 16.0 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	11.517	11.525	0.0079
551	1e+12	NDD	11.305	11.316	0.0109
552	1e+12	NDD	11.621	11.637	0.0169
553	5e+12	NDD	11.537	11.541	0.004
554	5e+12	NDD	11.554	11.553	-0.0017
555	5e+12	NDD	11.493	11.491	-0.0016
556	1e+13	NDD	11.37	11.358	-0.0119
557	1e+13	NDD	11.45	11.44	-0.0092
558	1e+13	NDD	11.421	11.4	-0.0216
559	0	NDD, Ctrl	11.612	11.648	0.0368

NDD vs Post - Pre Exposure Delta

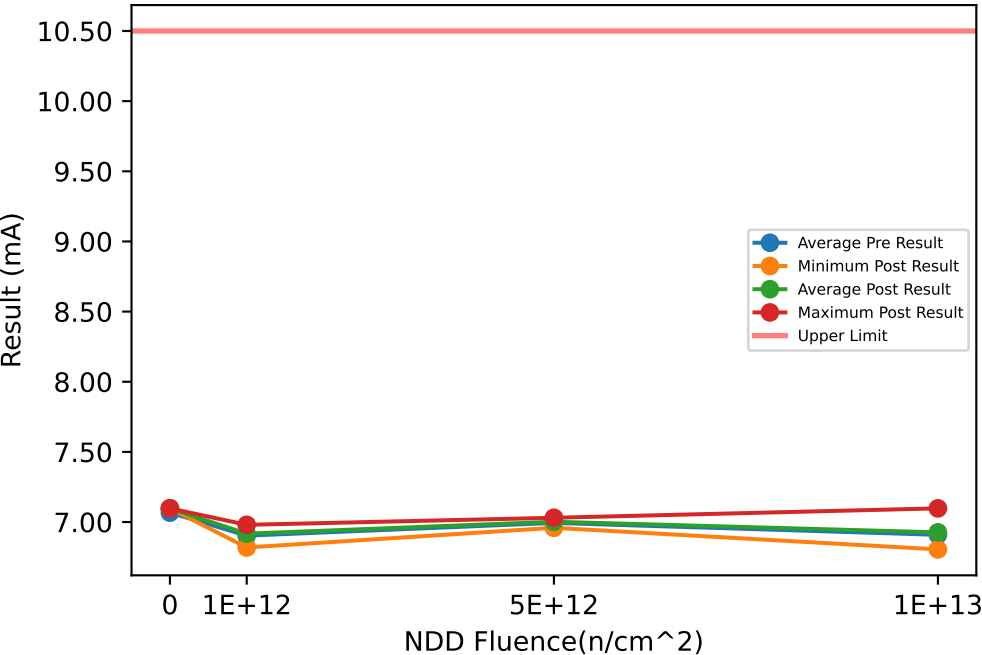


Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	11.612	11.612	11.612		11.648	11.648	11.648		0.0368	0.0368	0.0368	
1e+12	11.305	11.481	11.621	0.16092	11.316	11.493	11.637	0.16323	0.0079	0.0119	0.0169	0.0045826
5e+12	11.493	11.528	11.554	0.031674	11.491	11.528	11.553	0.032583	-0.0017	0.00023333	0.004	0.0032624
1e+13	11.37	11.414	11.45	0.040232	11.358	11.399	11.44	0.04105	-0.0216	-0.014233	-0.0092	0.006521

Device Test: 36.11 I_OP_HS_PWM_2MHZ(Iop HS BOOT PWM 2MHz VIN_12V)

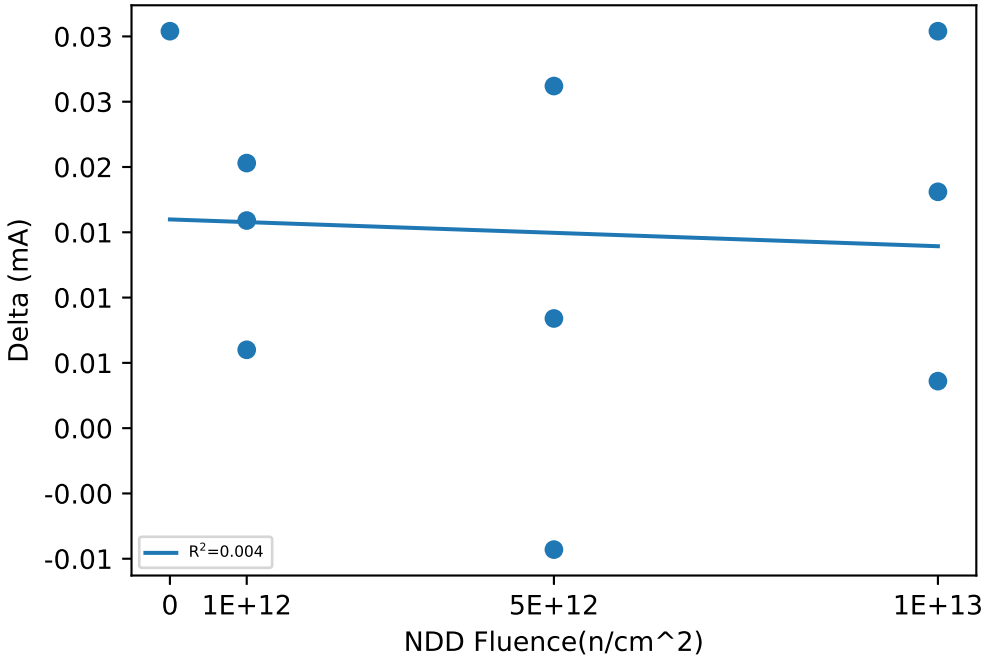
NDD vs Result Stats



Test Results (Upper Limit = 10.5 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	6.9365	6.9524	0.0159
551	1e+12	NDD	6.7983	6.8186	0.0203
552	1e+12	NDD	6.9741	6.9801	0.006
553	5e+12	NDD	7.0042	7.0304	0.0262
554	5e+12	NDD	7.0086	7.017	0.0084
555	5e+12	NDD	6.9684	6.9591	-0.0093
556	1e+13	NDD	6.8014	6.805	0.0036
557	1e+13	NDD	6.8585	6.8766	0.0181
558	1e+13	NDD	7.067	7.0974	0.0304
559	0	NDD, Ctrl	7.0671	7.0975	0.0304

NDD vs Post - Pre Exposure Delta

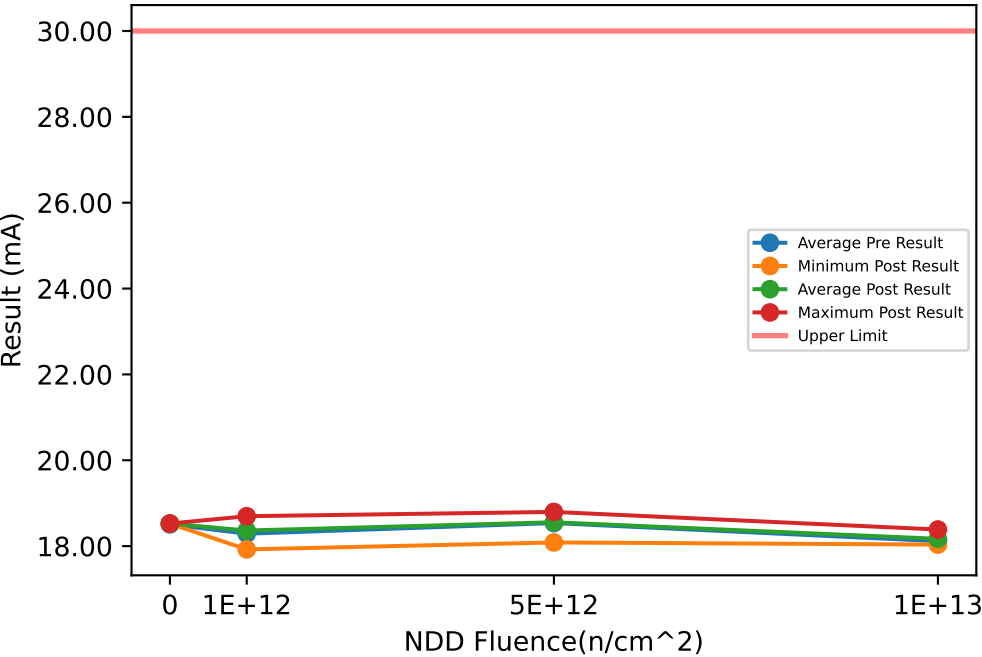


Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0671	7.0671	7.0671		7.0975	7.0975	7.0975		0.0304	0.0304	0.0304	
1e+12	6.7983	6.903	6.9741	0.092573	6.8186	6.917	6.9801	0.086364	0.006	0.014067	0.0203	0.0073242
5e+12	6.9684	6.9937	7.0086	0.022049	6.9591	7.0022	7.0304	0.037894	-0.0093	0.0084333	0.0262	0.01775
1e+13	6.8014	6.909	7.067	0.13981	6.805	6.9263	7.0974	0.15241	0.0036	0.017367	0.0304	0.013415

Device Test: 36.12 I_OP_LS_PWM_5MHZ(lop LS VIN PWM 5MHz VIN_12V)

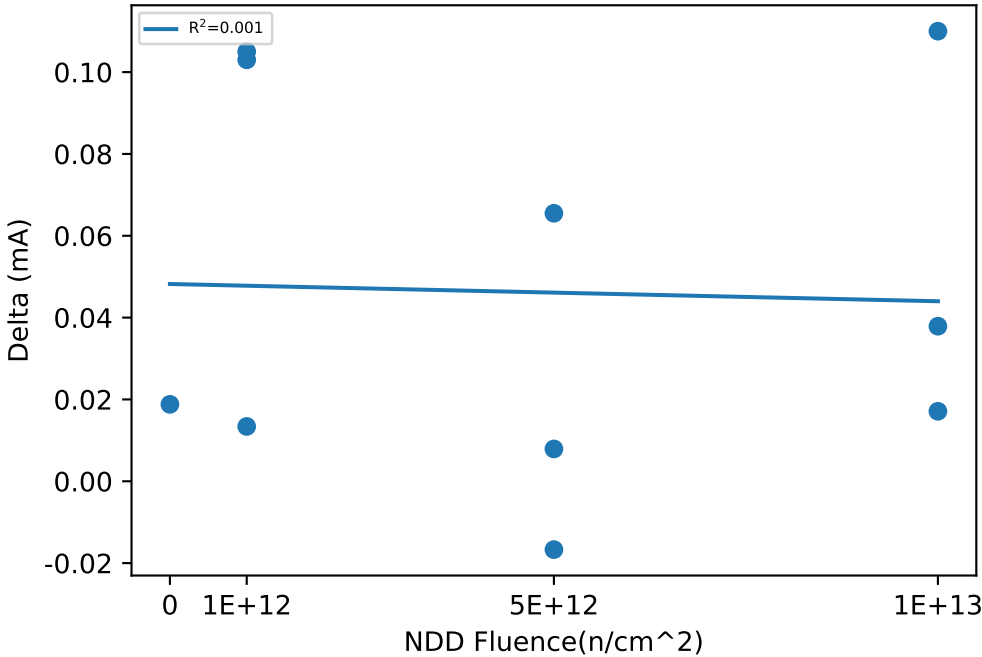
NDD vs Result Stats



Test Results (Upper Limit = 30.0 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	18.363	18.468	0.105
551	1e+12	NDD	17.91	17.924	0.0134
552	1e+12	NDD	18.594	18.697	0.103
553	5e+12	NDD	18.777	18.785	0.0079
554	5e+12	NDD	18.813	18.797	-0.0167
555	5e+12	NDD	18.02	18.086	0.0655
556	1e+13	NDD	18.37	18.387	0.0171
557	1e+13	NDD	17.979	18.089	0.11
558	1e+13	NDD	17.998	18.036	0.0379
559	0	NDD, Ctrl	18.506	18.525	0.0188

NDD vs Post - Pre Exposure Delta

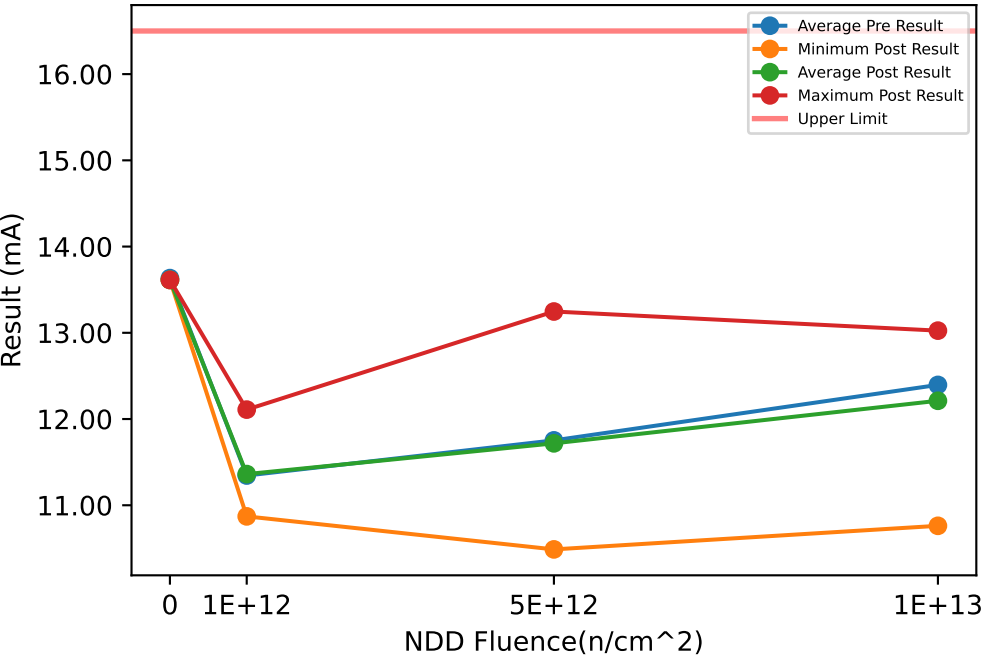


Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	18.506	18.506	18.506		18.525	18.525	18.525		0.0188	0.0188	0.0188	
1e+12	17.91	18.289	18.594	0.34788	17.924	18.363	18.697	0.39731	0.0134	0.0738	0.105	0.052317
5e+12	18.02	18.537	18.813	0.44768	18.086	18.556	18.797	0.40699	-0.0167	0.0189	0.0655	0.04219
1e+13	17.979	18.116	18.37	0.22026	18.036	18.171	18.387	0.18913	0.0171	0.055	0.11	0.048754

Device Test: 36.13 I_OP_HS_PWM_5MHZ(Iop HS BOOT PWM 5MHz VIN_12V)

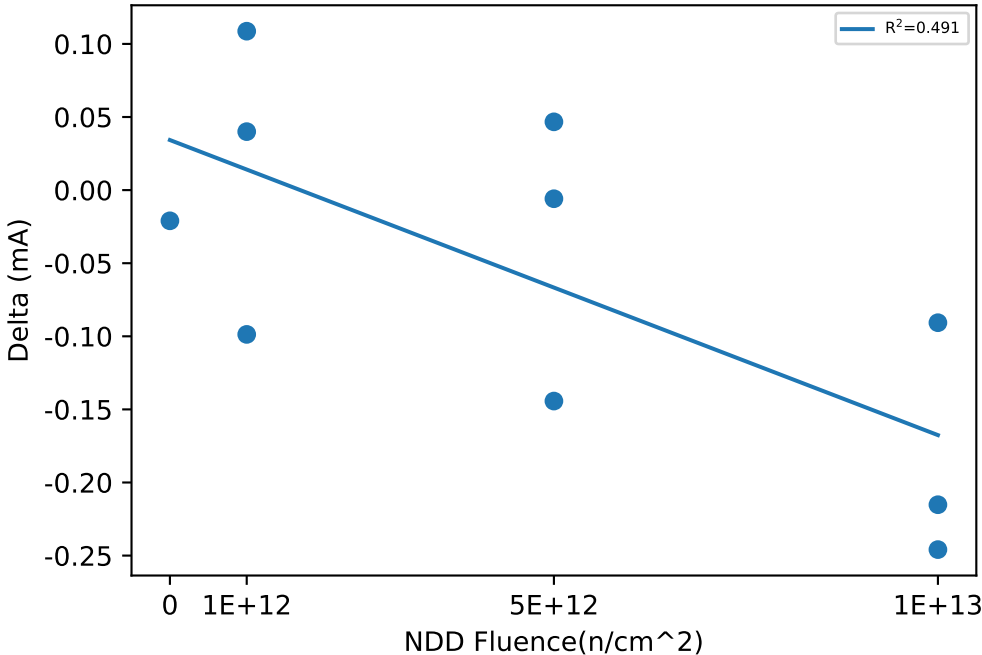
NDD vs Result Stats



Test Results (Upper Limit = 16.5 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	10.995	11.104	0.1087
551	1e+12	NDD	10.831	10.871	0.04
552	1e+12	NDD	12.208	12.109	-0.0987
553	5e+12	NDD	11.425	11.419	-0.0059
554	5e+12	NDD	10.441	10.488	0.0467
555	5e+12	NDD	13.391	13.247	-0.1443
556	1e+13	NDD	10.852	10.761	-0.0907
557	1e+13	NDD	13.271	13.025	-0.2459
558	1e+13	NDD	13.063	12.848	-0.2152
559	0	NDD, Ctrl	13.634	13.613	-0.021

NDD vs Post - Pre Exposure Delta

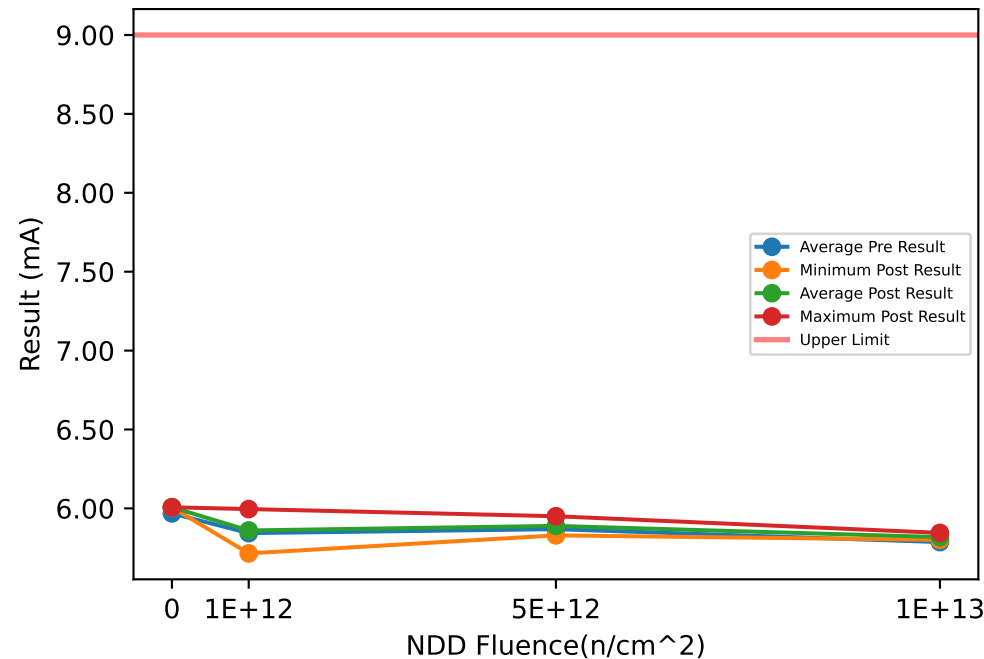


Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	13.634	13.634	13.634		13.613	13.613	13.613		-0.021	-0.021	-0.021	
1e+12	10.831	11.345	12.208	0.75198	10.871	11.361	12.109	0.65797	-0.0987	0.016667	0.1087	0.10565
5e+12	10.441	11.752	13.391	1.5019	10.488	11.718	13.247	1.4035	-0.1443	-0.0345	0.0467	0.09866
1e+13	10.852	12.396	13.271	1.3406	10.761	12.212	13.025	1.259	-0.2459	-0.18393	-0.0907	0.082189

Device Test: 36.14 I_OP_LS_IIM_500KHZ_INTERLOCK(Iop LS VIN IIM Interlock 500kHz VIN_12V)

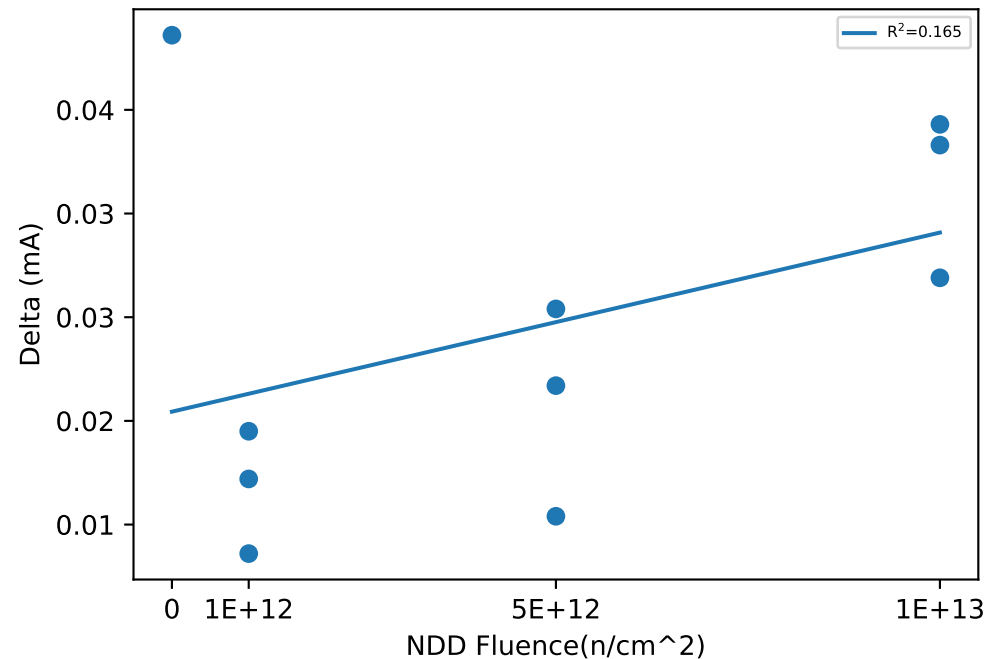
NDD vs Result Stats



Test Results (Upper Limit = 9.0 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	5.8528	5.87	0.0172
551	1e+12	NDD	5.7012	5.7148	0.0136
552	1e+12	NDD	5.9762	5.9957	0.0195
553	5e+12	NDD	5.8628	5.8882	0.0254
554	5e+12	NDD	5.9349	5.9503	0.0154
555	5e+12	NDD	5.8073	5.829	0.0217
556	1e+13	NDD	5.7743	5.8086	0.0343
557	1e+13	NDD	5.7674	5.8007	0.0333
558	1e+13	NDD	5.8179	5.8448	0.0269
559	0	NDD, Ctrl	5.9685	6.0071	0.0386

NDD vs Post - Pre Exposure Delta

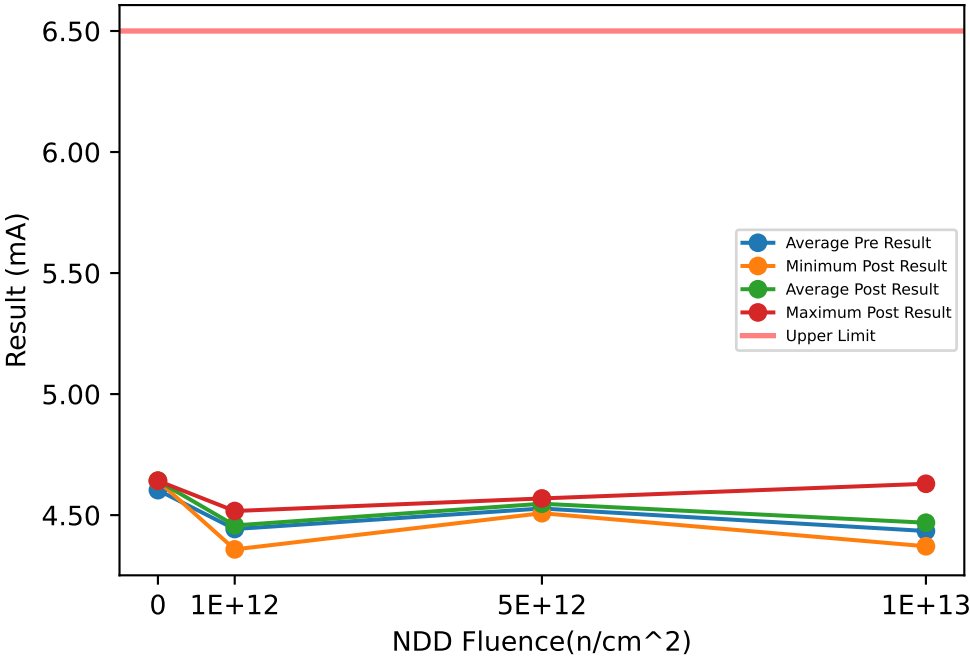


Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.9685	5.9685	5.9685		6.0071	6.0071	6.0071		0.0386	0.0386	0.0386	
1e+12	5.7012	5.8434	5.9762	0.13774	5.7148	5.8602	5.9957	0.14071	0.0136	0.016767	0.0195	0.0029738
5e+12	5.8073	5.8683	5.9349	0.06398	5.829	5.8892	5.9503	0.060656	0.0154	0.020833	0.0254	0.005056
1e+13	5.7674	5.7865	5.8179	0.027383	5.8007	5.818	5.8448	0.023515	0.0269	0.0315	0.0343	0.004015

Device Test: 36.15 I_OP_HS_IIM_500KHZ_INTERLOCK(Iop HS BOOT IIM Interlock 500kHz VIN_12V)

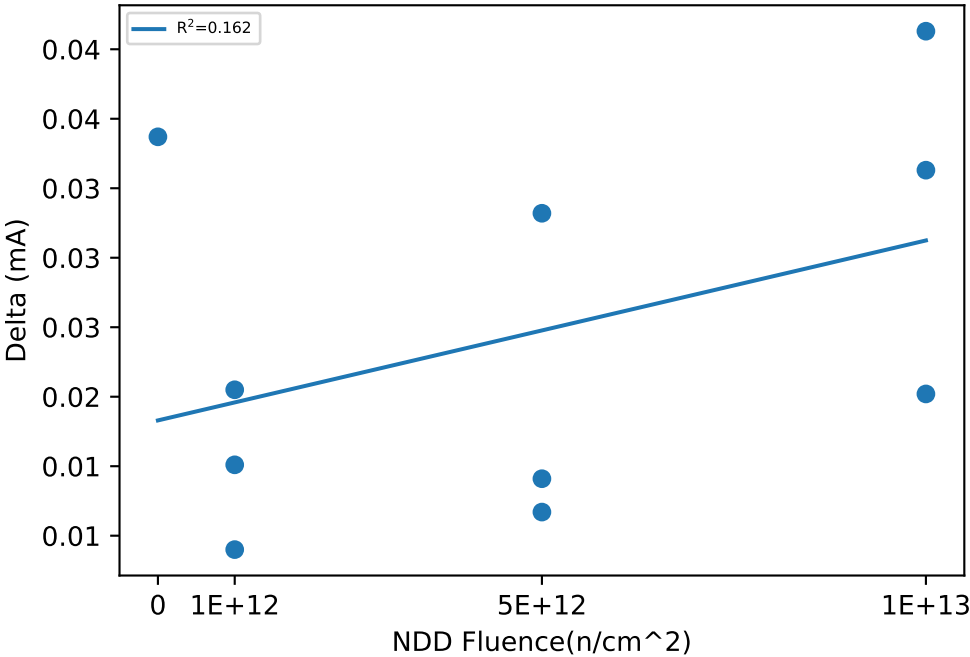
NDD vs Result Stats



Test Results (Upper Limit = 6.5 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.4818	4.4969	0.0151
551	1e+12	NDD	4.3379	4.3584	0.0205
552	1e+12	NDD	4.508	4.517	0.009
553	5e+12	NDD	4.5312	4.5644	0.0332
554	5e+12	NDD	4.5548	4.5689	0.0141
555	5e+12	NDD	4.4962	4.5079	0.0117
556	1e+13	NDD	4.3511	4.3713	0.0202
557	1e+13	NDD	4.3688	4.4051	0.0363
558	1e+13	NDD	4.5832	4.6295	0.0463
559	0	NDD, Ctrl	4.6032	4.6419	0.0387

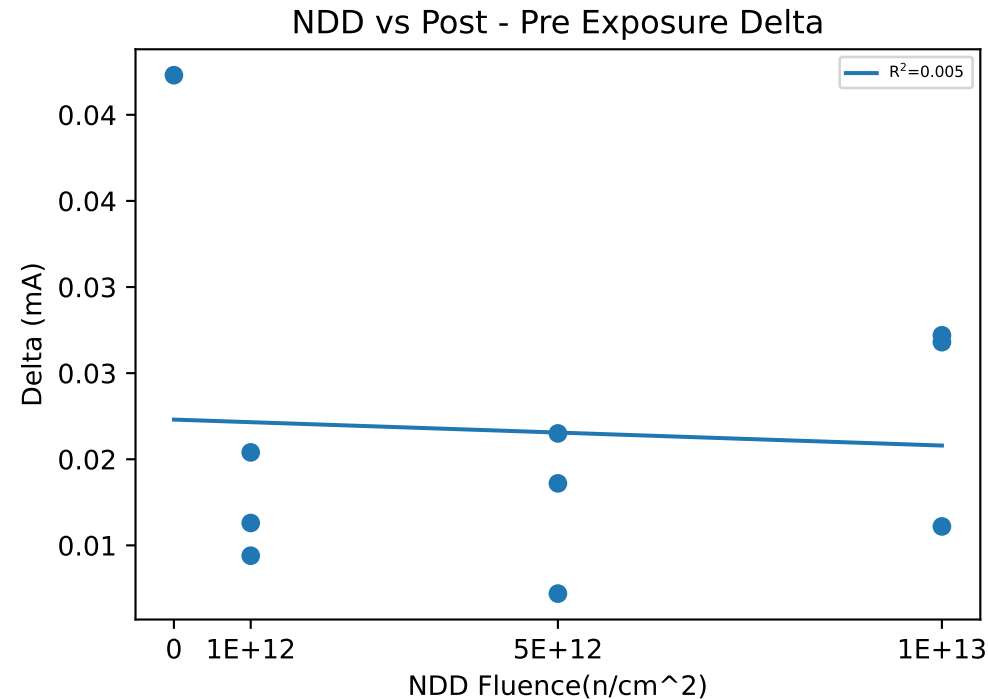
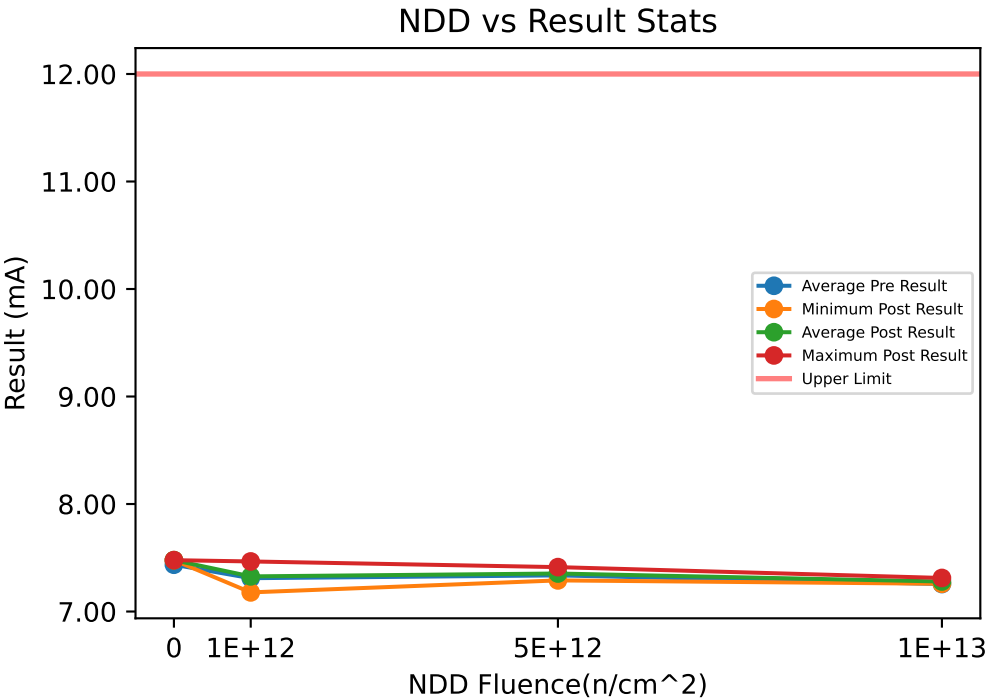
NDD vs Post - Pre Exposure Delta



Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.6032	4.6032	4.6032		4.6419	4.6419	4.6419		0.0387	0.0387	0.0387	
1e+12	4.3379	4.4426	4.508	0.091586	4.3584	4.4574	4.517	0.086352	0.009	0.014867	0.0205	0.0057535
5e+12	4.4962	4.5274	4.5548	0.029484	4.5079	4.5471	4.5689	0.033994	0.0117	0.019667	0.0332	0.011781
1e+13	4.3511	4.4344	4.5832	0.1292	4.3713	4.4686	4.6295	0.14034	0.0202	0.034267	0.0463	0.013168

Device Test: 36.16 I_OP_LS_IIM_1MHZ_INTERLOCK(Iop LS VIN IIM Interlock 1MHz VIN_12V)



Test Results (Upper Limit = 12.0 (mA))

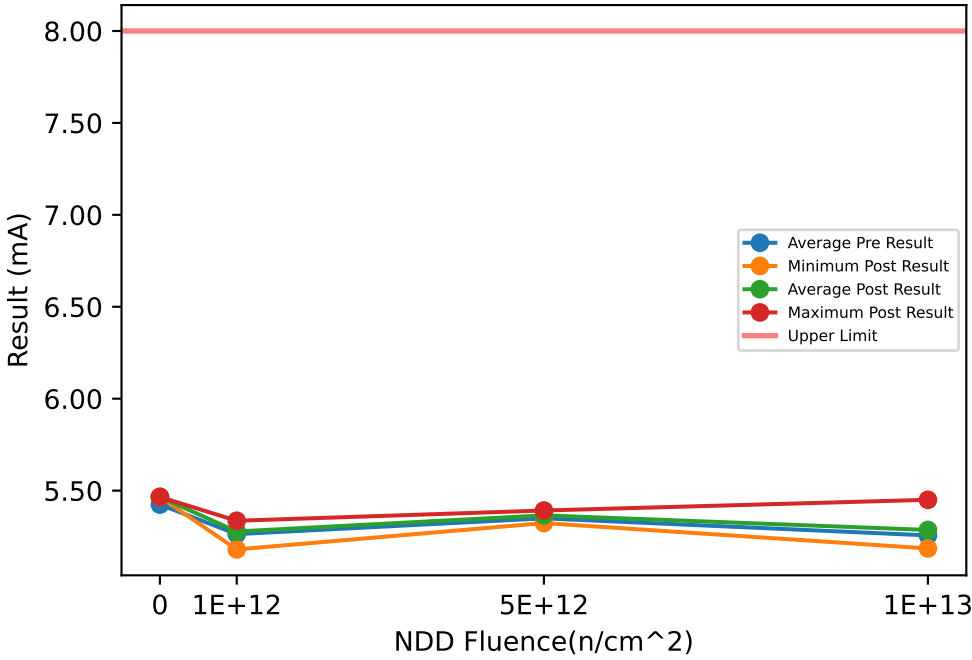
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	7.3208	7.3371	0.0163
551	1e+12	NDD	7.1635	7.1779	0.0144
552	1e+12	NDD	7.4454	7.4658	0.0204
553	5e+12	NDD	7.3367	7.3582	0.0215
554	5e+12	NDD	7.4008	7.413	0.0122
555	5e+12	NDD	7.2709	7.2895	0.0186
556	1e+13	NDD	7.2314	7.2582	0.0268
557	1e+13	NDD	7.2399	7.2671	0.0272
558	1e+13	NDD	7.2961	7.3122	0.0161
559	0	NDD, Ctrl	7.4353	7.4776	0.0423

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.4353	7.4353	7.4353		7.4776	7.4776	7.4776		0.0423	0.0423	0.0423	
1e+12	7.1635	7.3099	7.4454	0.14127	7.1779	7.3269	7.4658	0.14422	0.0144	0.017033	0.0204	0.0030665
5e+12	7.2709	7.3361	7.4008	0.064952	7.2895	7.3536	7.413	0.06188	0.0122	0.017433	0.0215	0.0047585
1e+13	7.2314	7.2558	7.2961	0.035159	7.2582	7.2792	7.3122	0.028952	0.0161	0.023367	0.0272	0.0062963

Device Test: 36.17 I_OP_HS_IIM_1MHZ_INTERLOCK(Iop HS BOOT IIM Interlock 1MHz VIN_12V)

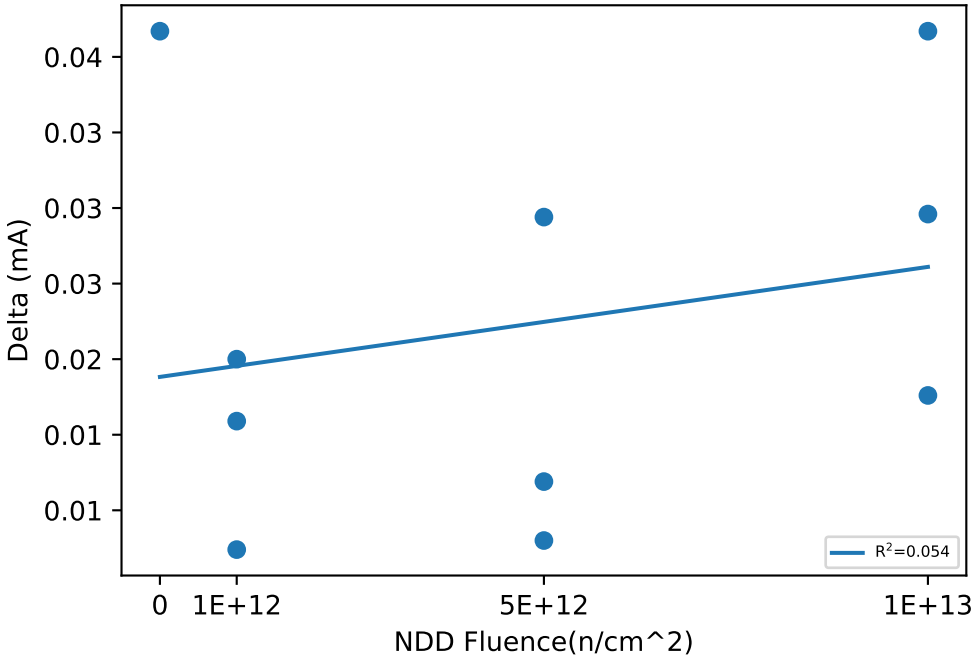
NDD vs Result Stats



Test Results (Upper Limit = 8.0 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	5.3011	5.317	0.0159
551	1e+12	NDD	5.1603	5.1803	0.02
552	1e+12	NDD	5.3286	5.336	0.0074
553	5e+12	NDD	5.3519	5.3813	0.0294
554	5e+12	NDD	5.3799	5.3918	0.0119
555	5e+12	NDD	5.3155	5.3235	0.008
556	1e+13	NDD	5.1679	5.1855	0.0176
557	1e+13	NDD	5.1933	5.2229	0.0296
558	1e+13	NDD	5.4083	5.45	0.0417
559	0	NDD, Ctrl	5.424	5.4657	0.0417

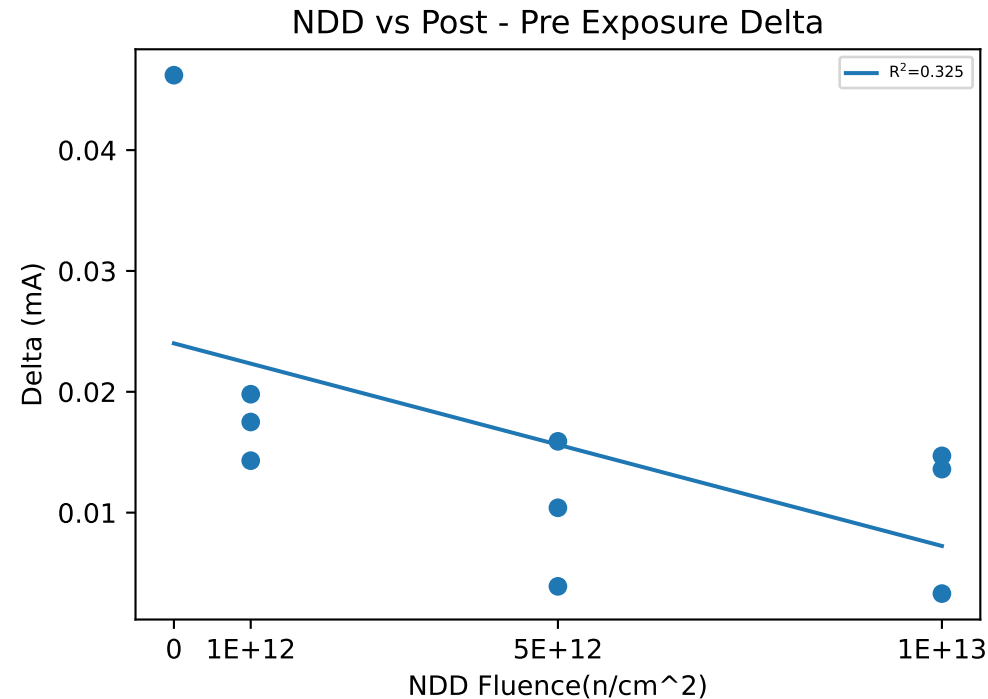
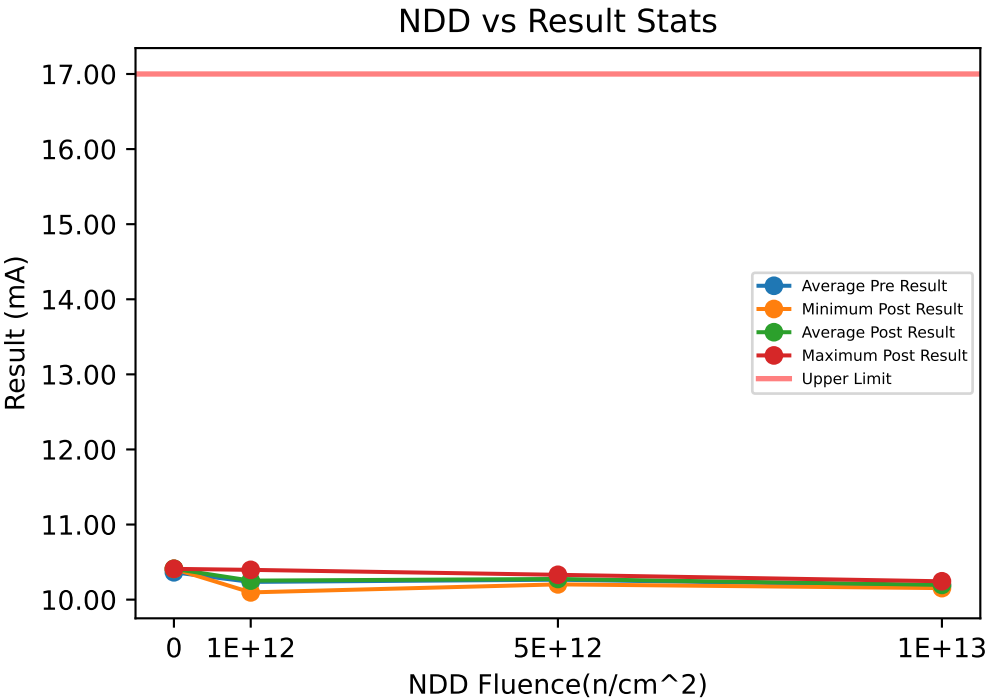
NDD vs Post - Pre Exposure Delta



Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.424	5.424	5.424		5.4657	5.4657	5.4657		0.0417	0.0417	0.0417	
1e+12	5.1603	5.2633	5.3286	0.090283	5.1803	5.2778	5.336	0.084942	0.0074	0.014433	0.02	0.0064268
5e+12	5.3155	5.3491	5.3799	0.032291	5.3235	5.3655	5.3918	0.036779	0.008	0.016433	0.0294	0.011398
1e+13	5.1679	5.2565	5.4083	0.13207	5.1855	5.2861	5.45	0.14314	0.0176	0.029633	0.0417	0.01205

Device Test: 36.18 I_OP_LS_IIM_2MHZ_INTERLOCK(Iop LS VIN IIM Interlock 2MHz VIN_12V)



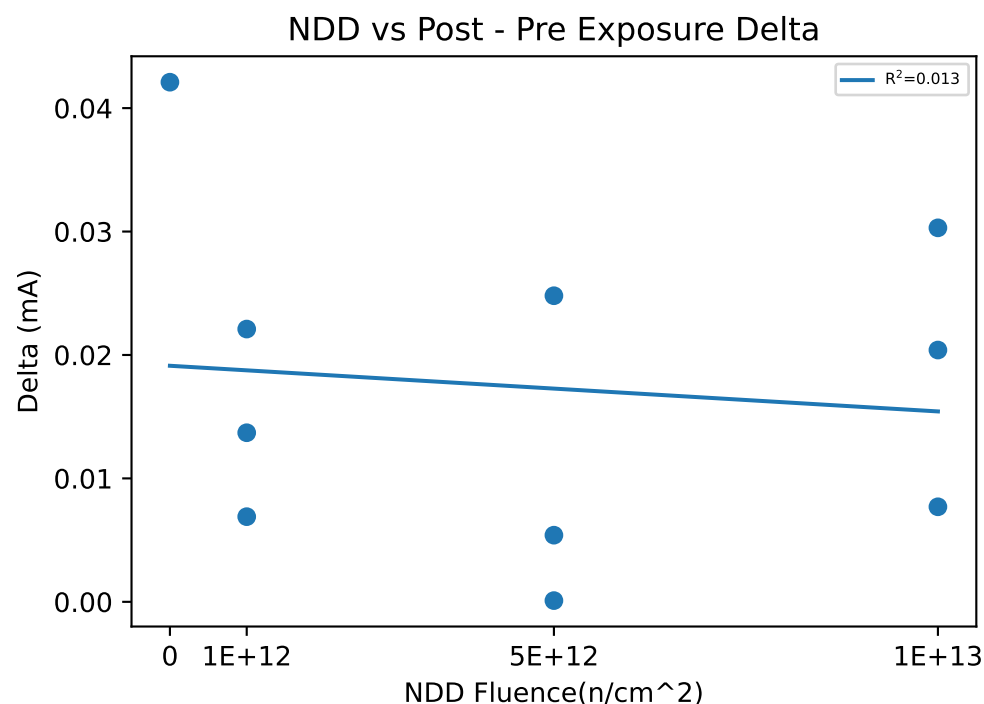
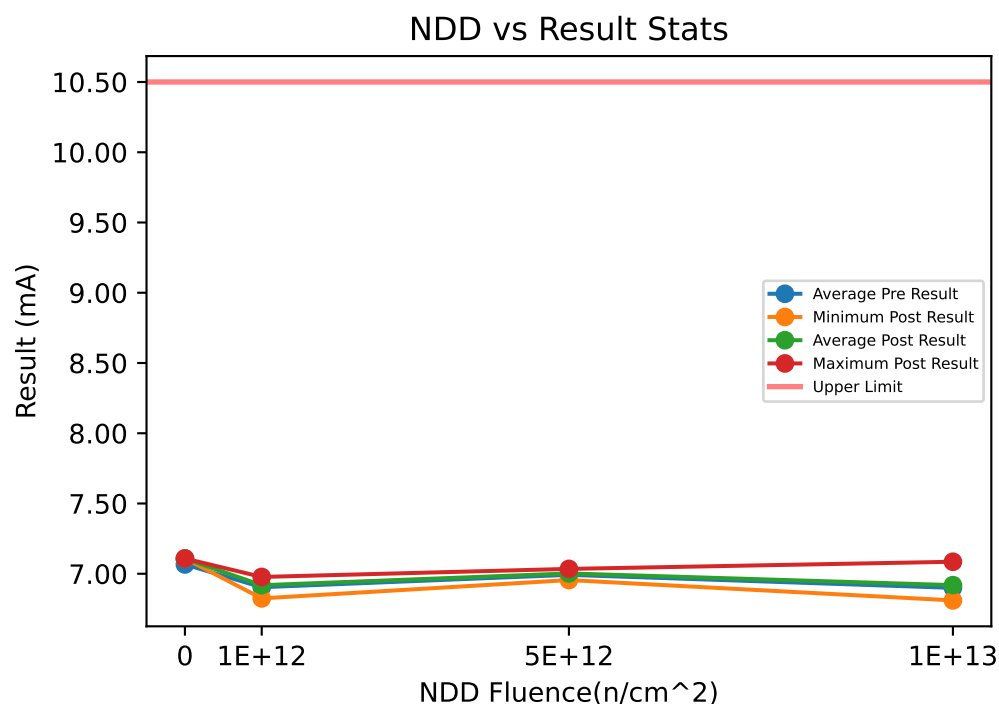
Test Results (Upper Limit = 17.0 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	10.249	10.267	0.0175
551	1e+12	NDD	10.082	10.096	0.0143
552	1e+12	NDD	10.377	10.396	0.0198
553	5e+12	NDD	10.276	10.292	0.0159
554	5e+12	NDD	10.327	10.331	0.0039
555	5e+12	NDD	10.193	10.203	0.0104
556	1e+13	NDD	10.139	10.153	0.0147
557	1e+13	NDD	10.177	10.191	0.0136
558	1e+13	NDD	10.241	10.244	0.0033
559	0	NDD, Ctrl	10.364	10.41	0.0462

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	10.364	10.364	10.364		10.41	10.41	10.41		0.0462	0.0462	0.0462	
1e+12	10.082	10.236	10.377	0.14775	10.096	10.253	10.396	0.15051	0.0143	0.0172	0.0198	0.0027622
5e+12	10.193	10.265	10.327	0.067596	10.203	10.275	10.331	0.065302	0.0039	0.010067	0.0159	0.0060069
1e+13	10.139	10.186	10.241	0.051821	10.153	10.196	10.244	0.045839	0.0033	0.010533	0.0147	0.0062883

Device Test: 36.19 I_OP_HS_IIM_2MHZ_INTERLOCK(Iop HS BOOT IIM Interlock 2MHz VIN_12V)



Test Results (Upper Limit = 10.5 (mA))

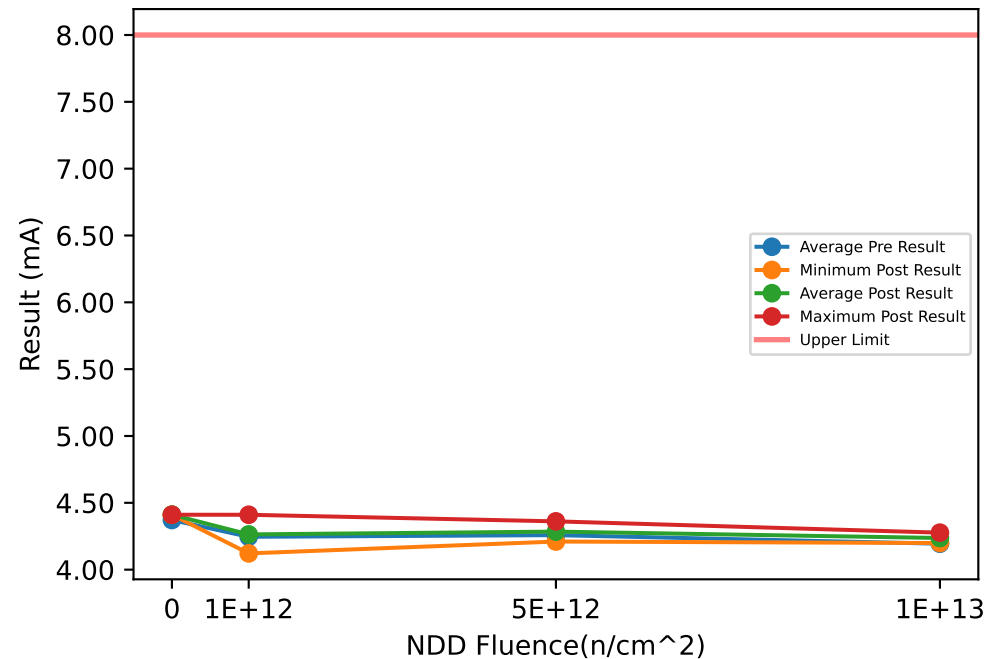
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	6.9396	6.9533	0.0137
551	1e+12	NDD	6.8026	6.8247	0.0221
552	1e+12	NDD	6.9703	6.9772	0.0069
553	5e+12	NDD	6.9925	7.0173	0.0248
554	5e+12	NDD	7.0291	7.0345	0.0054
555	5e+12	NDD	6.9549	6.955	0.0001
556	1e+13	NDD	6.8026	6.8103	0.0077
557	1e+13	NDD	6.8408	6.8612	0.0204
558	1e+13	NDD	7.055	7.0853	0.0303
559	0	NDD, Ctrl	7.0662	7.1083	0.0421

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0662	7.0662	7.0662		7.1083	7.1083	7.1083		0.0421	0.0421	0.0421	
1e+12	6.8026	6.9042	6.9703	0.089289	6.8247	6.9184	6.9772	0.082022	0.0069	0.014233	0.0221	0.007614
5e+12	6.9549	6.9922	7.0291	0.037101	6.955	7.0023	7.0345	0.041828	0.0001	0.0101	0.0248	0.013003
1e+13	6.8026	6.8995	7.055	0.13604	6.8103	6.9189	7.0853	0.14631	0.0077	0.019467	0.0303	0.011329

Device Test: 36.2 IQ_LS_IIM_INTERLOCK(Iq LS VIN IIM Interlock VIN_12V)

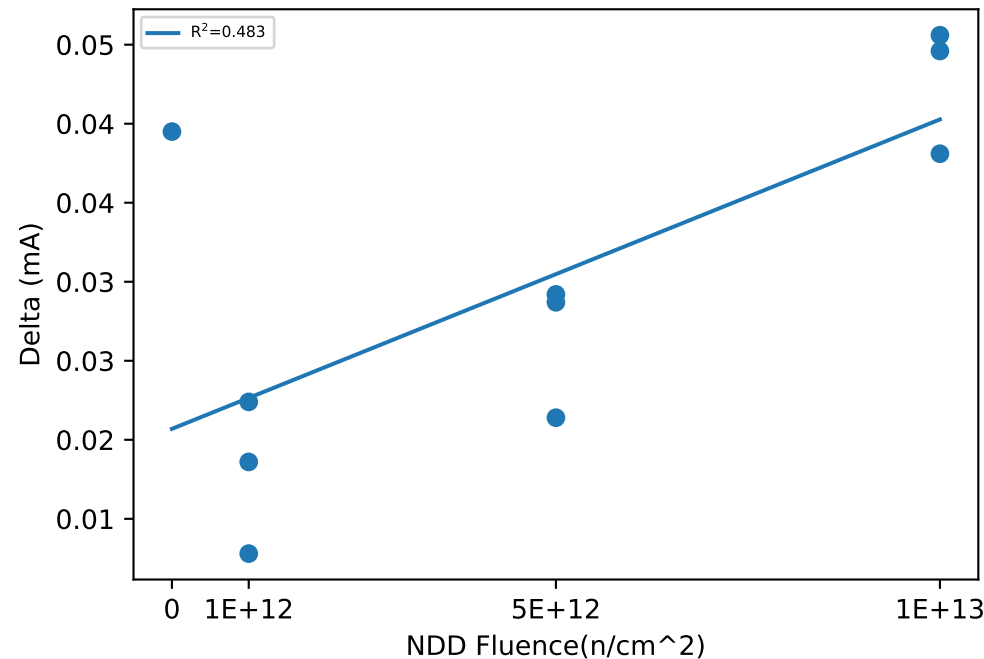
NDD vs Result Stats



Test Results (Upper Limit = 8.0 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.2403	4.2589	0.0186
551	1e+12	NDD	4.1088	4.1216	0.0128
552	1e+12	NDD	4.3882	4.4106	0.0224
553	5e+12	NDD	4.2535	4.2822	0.0287
554	5e+12	NDD	4.3399	4.3613	0.0214
555	5e+12	NDD	4.1811	4.2103	0.0292
556	1e+13	NDD	4.1888	4.2344	0.0456
557	1e+13	NDD	4.1546	4.1992	0.0446
558	1e+13	NDD	4.2387	4.2768	0.0381
559	0	NDD, Ctrl	4.3713	4.4108	0.0395

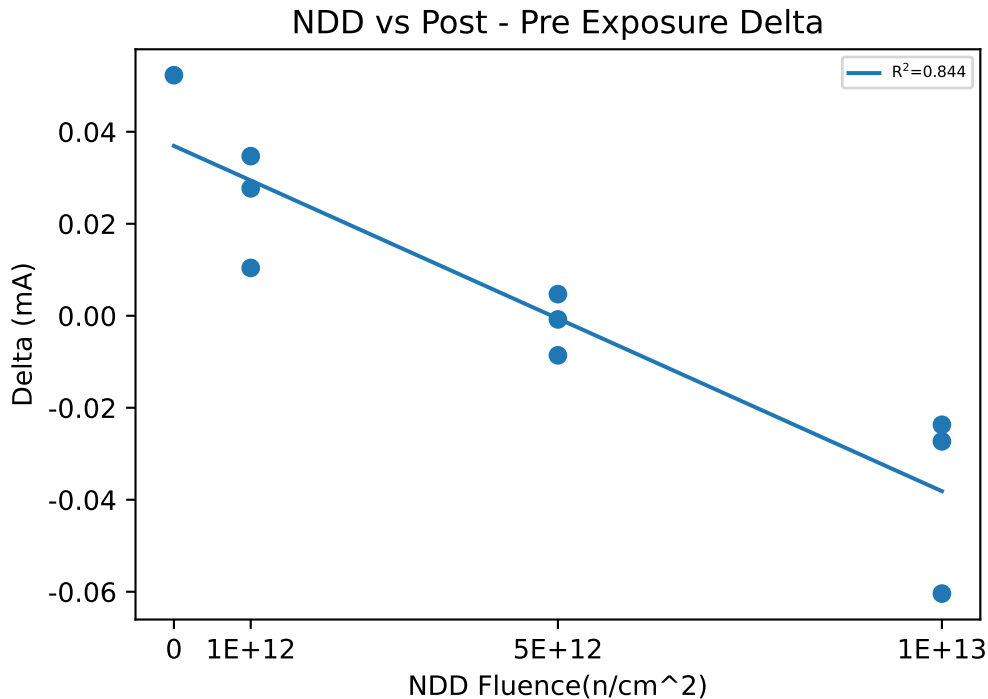
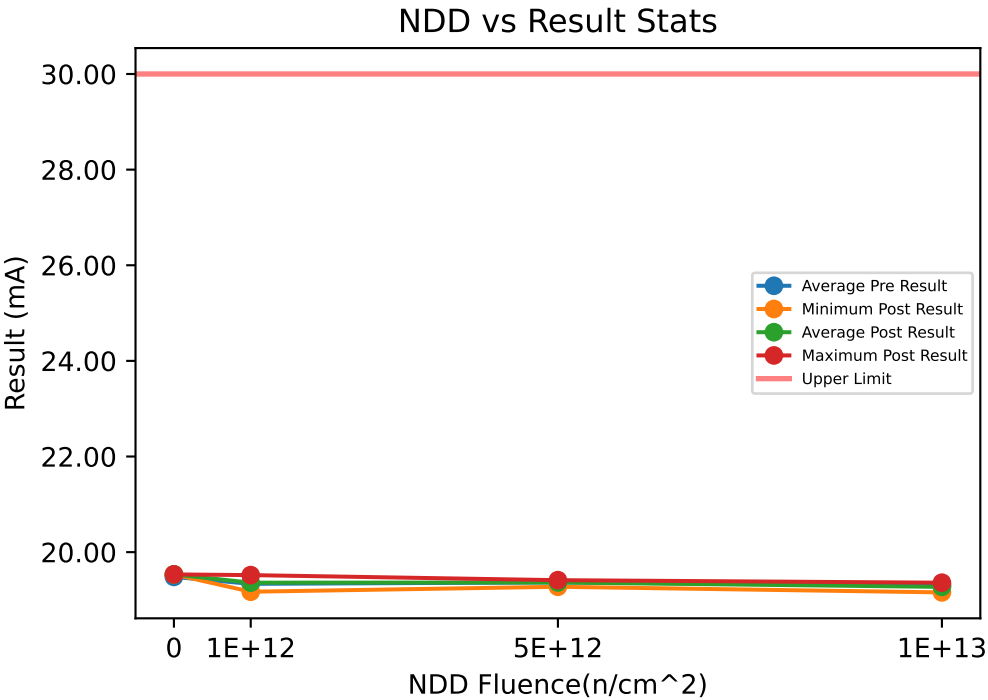
NDD vs Post - Pre Exposure Delta



Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.3713	4.3713	4.3713		4.4108	4.4108	4.4108		0.0395	0.0395	0.0395	
1e+12	4.1088	4.2458	4.3882	0.13978	4.1216	4.2637	4.4106	0.14456	0.0128	0.017933	0.0224	0.0048346
5e+12	4.1811	4.2582	4.3399	0.079503	4.2103	4.2846	4.3613	0.075529	0.0214	0.026433	0.0292	0.0043662
1e+13	4.1546	4.194	4.2387	0.042294	4.1992	4.2368	4.2768	0.038856	0.0381	0.042767	0.0456	0.0040723

Device Test: 36.20 I_OP_LS_IIM_5MHZ_INTERLOCK(Iop LS VIN IIM Interlock 5MHz VIN_12V)

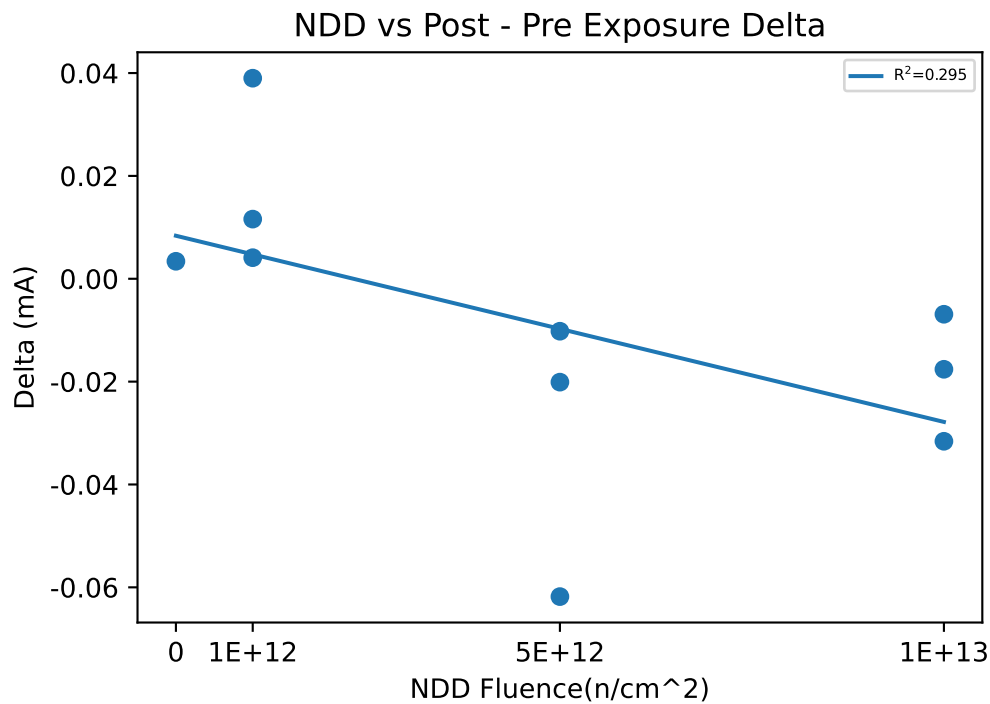
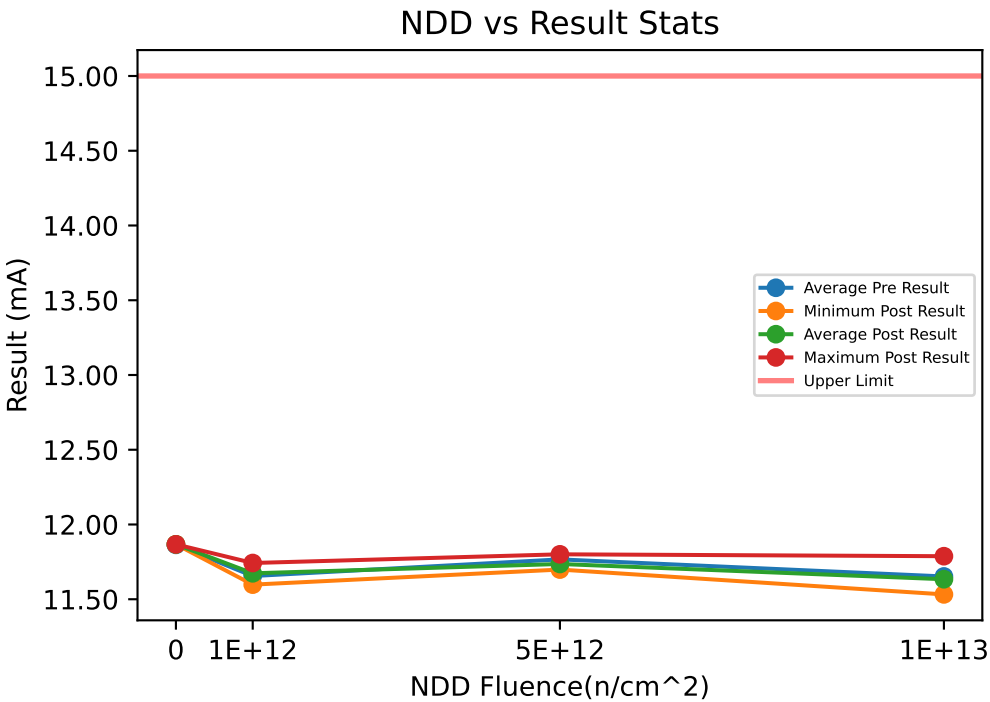


Test Results (Upper Limit = 30.0 (mA))					
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	19.364	19.392	0.0277
551	1e+12	NDD	19.162	19.172	0.0104
552	1e+12	NDD	19.485	19.52	0.0347
553	5e+12	NDD	19.409	19.414	0.0047
554	5e+12	NDD	19.416	19.407	-0.0086
555	5e+12	NDD	19.277	19.276	-0.0008
556	1e+13	NDD	19.182	19.158	-0.0237
557	1e+13	NDD	19.329	19.302	-0.0273
558	1e+13	NDD	19.421	19.361	-0.0604
559	0	NDD, Ctrl	19.482	19.534	0.0523

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	19.482	19.482	19.482		19.534	19.534	19.534		0.0523	0.0523	0.0523	
1e+12	19.162	19.337	19.485	0.16323	19.172	19.361	19.52	0.17569	0.0104	0.024267	0.0347	0.012509
5e+12	19.277	19.367	19.416	0.078447	19.276	19.366	19.414	0.077781	-0.0086	-0.0015667	0.0047	0.0066831
1e+13	19.182	19.311	19.421	0.12088	19.158	19.274	19.361	0.1044	-0.0604	-0.037133	-0.0237	0.02023

Device Test: 36.21 I_OP_HS_IIM_5MHZ_INTERLOCK(Iop HS BOOT IIM Interlock 5MHz VIN_12V)



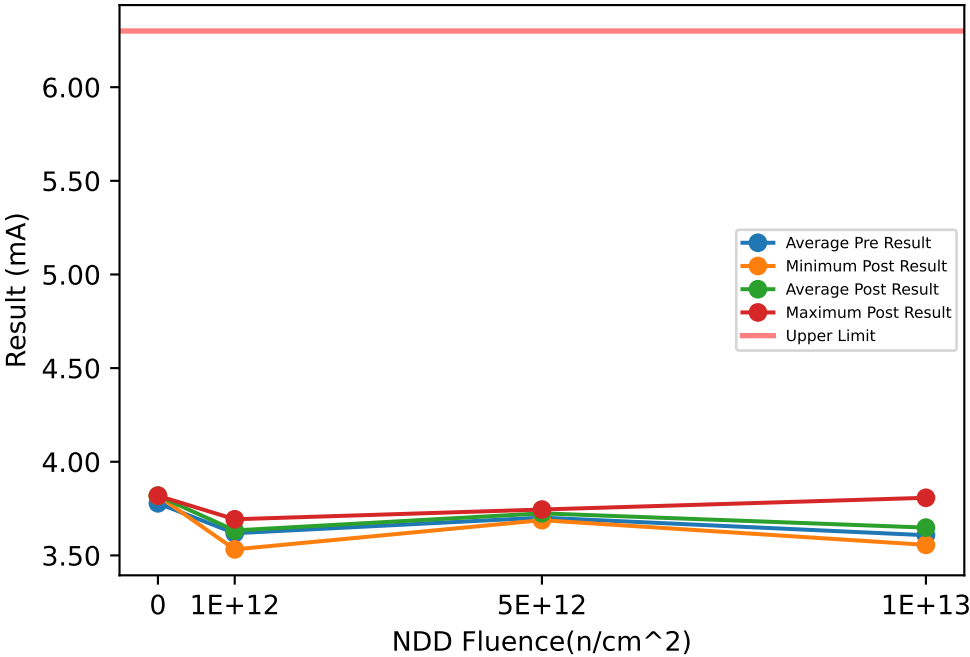
Test Results (Upper Limit = 15.0 (mA))					
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	11.669	11.68	0.0116
551	1e+12	NDD	11.559	11.598	0.039
552	1e+12	NDD	11.738	11.742	0.0041
553	5e+12	NDD	11.729	11.709	-0.0201
554	5e+12	NDD	11.811	11.8	-0.0102
555	5e+12	NDD	11.76	11.698	-0.0618
556	1e+13	NDD	11.564	11.532	-0.0316
557	1e+13	NDD	11.599	11.581	-0.0176
558	1e+13	NDD	11.795	11.788	-0.0069
559	0	NDD, Ctrl	11.864	11.867	0.0034

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	11.864	11.864	11.864		11.867	11.867	11.867		0.0034	0.0034	0.0034	
1e+12	11.559	11.655	11.738	0.090554	11.598	11.673	11.742	0.072592	0.0041	0.018233	0.039	0.018371
5e+12	11.729	11.767	11.811	0.041358	11.698	11.736	11.8	0.056201	-0.0618	-0.0307	-0.0102	0.027384
1e+13	11.564	11.652	11.795	0.12447	11.532	11.634	11.788	0.13568	-0.0316	-0.0187	-0.0069	0.012387

Device Test: 36.3 IQ_HS_IIM_INTERLOCK(Iq HS BOOT IIM Interlock VIN_12V)

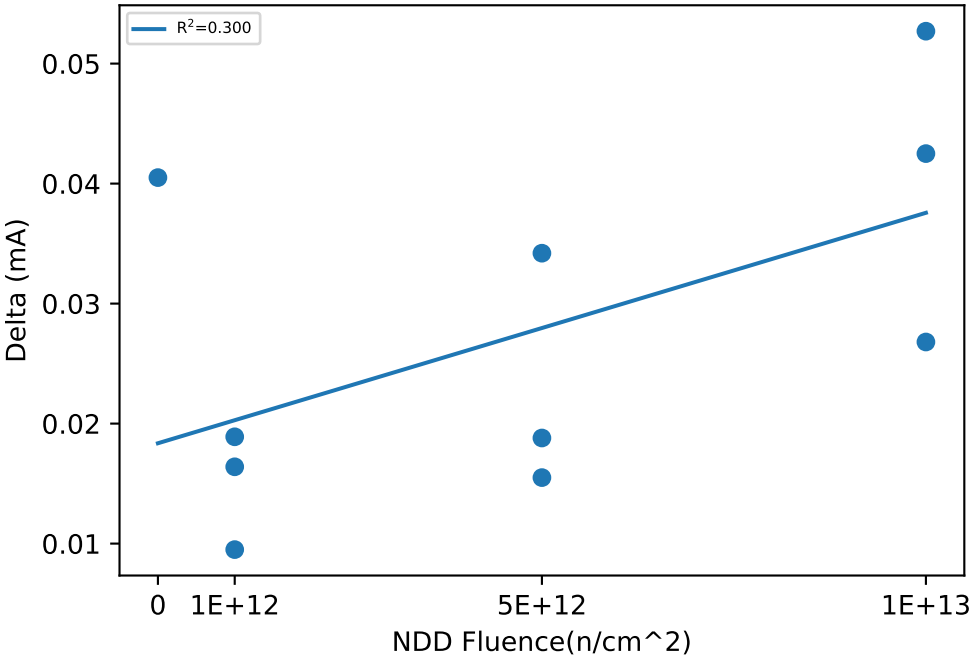
NDD vs Result Stats



Test Results (Upper Limit = 6.3 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	3.6586	3.675	0.0164
551	1e+12	NDD	3.5132	3.5321	0.0189
552	1e+12	NDD	3.6835	3.693	0.0095
553	5e+12	NDD	3.7068	3.741	0.0342
554	5e+12	NDD	3.7262	3.745	0.0188
555	5e+12	NDD	3.6726	3.6881	0.0155
556	1e+13	NDD	3.5294	3.5562	0.0268
557	1e+13	NDD	3.5391	3.5816	0.0425
558	1e+13	NDD	3.7549	3.8076	0.0527
559	0	NDD, Ctrl	3.7781	3.8186	0.0405

NDD vs Post - Pre Exposure Delta

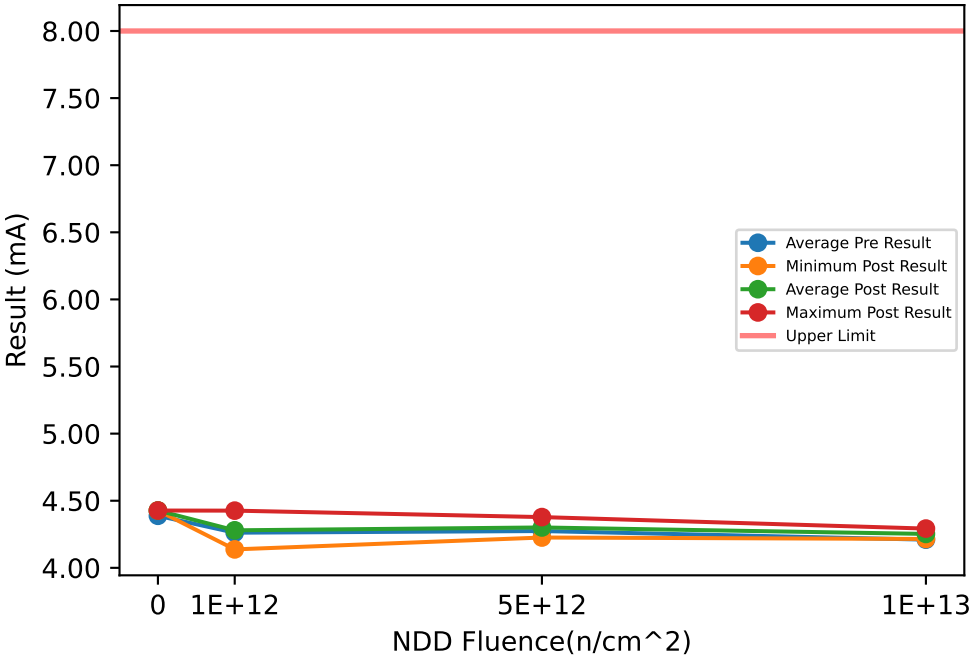


Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7781	3.7781	3.7781		3.8186	3.8186	3.8186		0.0405	0.0405	0.0405	
1e+12	3.5132	3.6184	3.6835	0.091981	3.5321	3.6334	3.693	0.08816	0.0095	0.014933	0.0189	0.0048686
5e+12	3.6726	3.7019	3.7262	0.027138	3.6881	3.7247	3.745	0.03176	0.0155	0.022833	0.0342	0.0099811
1e+13	3.5294	3.6078	3.7549	0.12748	3.5562	3.6485	3.8076	0.1384	0.0268	0.040667	0.0527	0.013047

Device Test: 36.4 IQ_LS_IIM_INTERLOCK_DIS(Iq LS VIN IIM Interlock Disable VIN_12V)

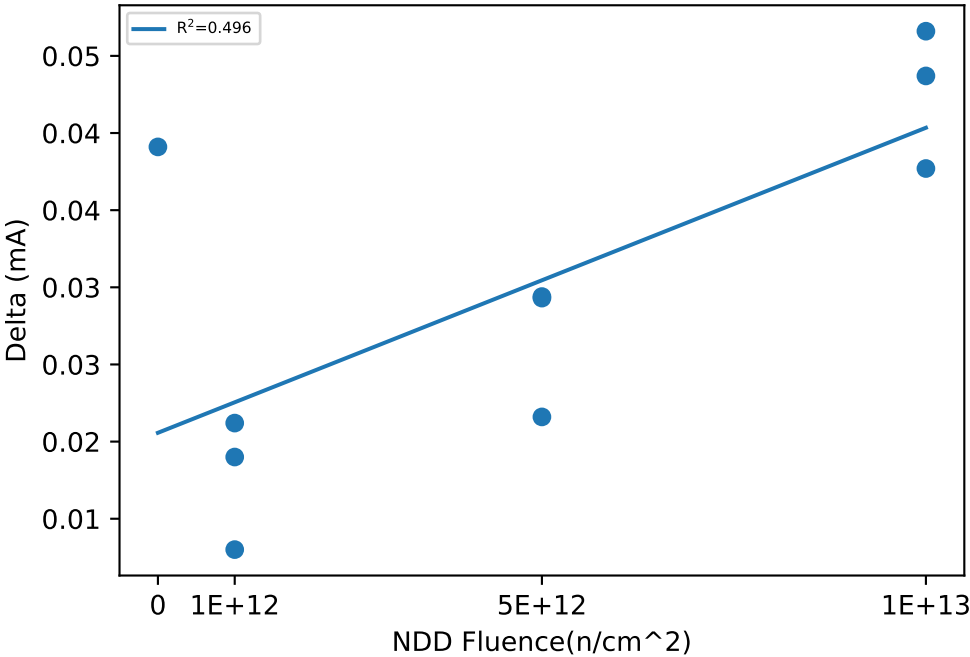
NDD vs Result Stats



Test Results (Upper Limit = 8.0 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.2562	4.2752	0.019
551	1e+12	NDD	4.1244	4.1374	0.013
552	1e+12	NDD	4.405	4.4262	0.0212
553	5e+12	NDD	4.2694	4.2987	0.0293
554	5e+12	NDD	4.3565	4.3781	0.0216
555	5e+12	NDD	4.1965	4.2259	0.0294
556	1e+13	NDD	4.2038	4.2504	0.0466
557	1e+13	NDD	4.1715	4.2152	0.0437
558	1e+13	NDD	4.2548	4.2925	0.0377
559	0	NDD, Ctrl	4.3879	4.427	0.0391

NDD vs Post - Pre Exposure Delta

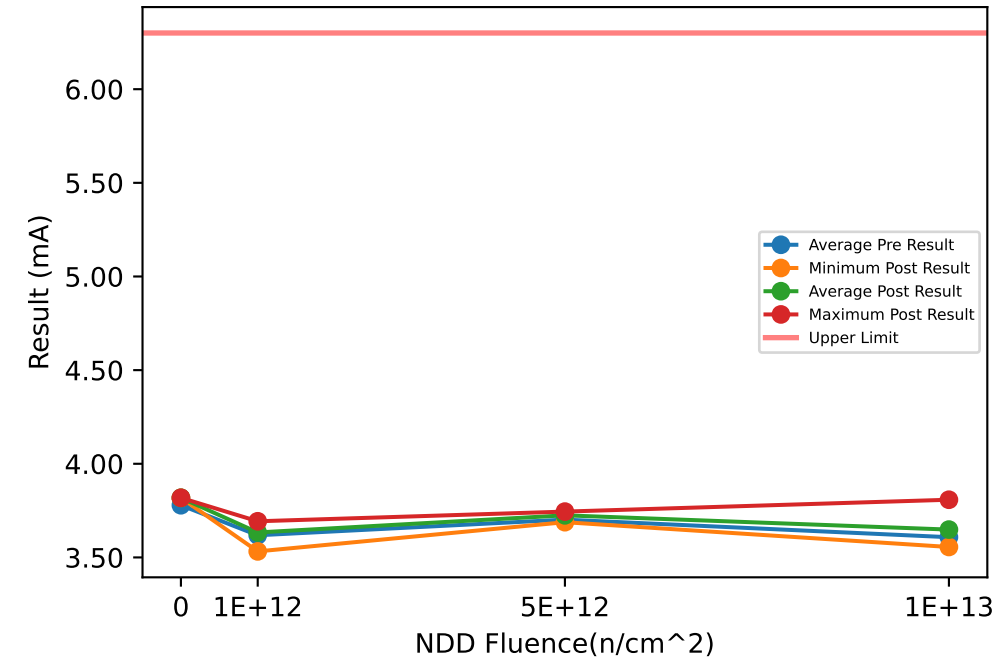


Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.3879	4.3879	4.3879		4.427	4.427	4.427		0.0391	0.0391	0.0391	
1e+12	4.1244	4.2619	4.405	0.14039	4.1374	4.2796	4.4262	0.14445	0.013	0.017733	0.0212	0.0042442
5e+12	4.1965	4.2741	4.3565	0.080105	4.2259	4.3009	4.3781	0.076124	0.0216	0.026767	0.0294	0.0044747
1e+13	4.1715	4.21	4.2548	0.041998	4.2152	4.2527	4.2925	0.038701	0.0377	0.042667	0.0466	0.0045391

Device Test: 36.5 IQ_HS_IIM_INTERLOCK_DIS(Iq HS BOOT IIM Interlock Disable VIN_12V)

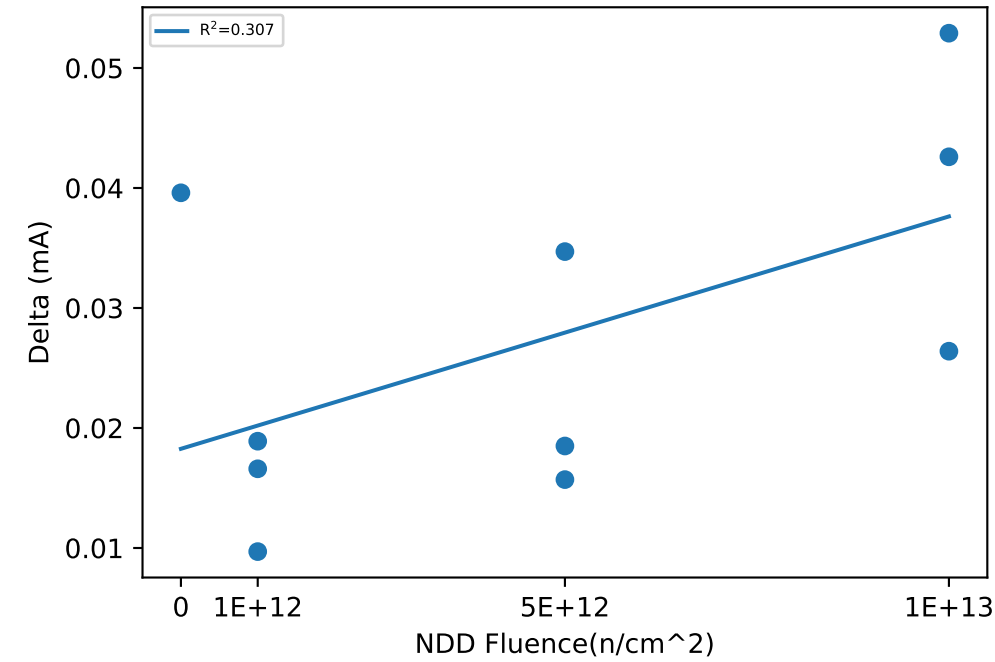
NDD vs Result Stats



Test Results (Upper Limit = 6.3 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	3.6582	3.6748	0.0166
551	1e+12	NDD	3.5133	3.5322	0.0189
552	1e+12	NDD	3.6833	3.693	0.0097
553	5e+12	NDD	3.7069	3.7416	0.0347
554	5e+12	NDD	3.7262	3.7447	0.0185
555	5e+12	NDD	3.6724	3.6881	0.0157
556	1e+13	NDD	3.5294	3.5558	0.0264
557	1e+13	NDD	3.5396	3.5822	0.0426
558	1e+13	NDD	3.7551	3.808	0.0529
559	0	NDD, Ctrl	3.7786	3.8182	0.0396

NDD vs Post - Pre Exposure Delta

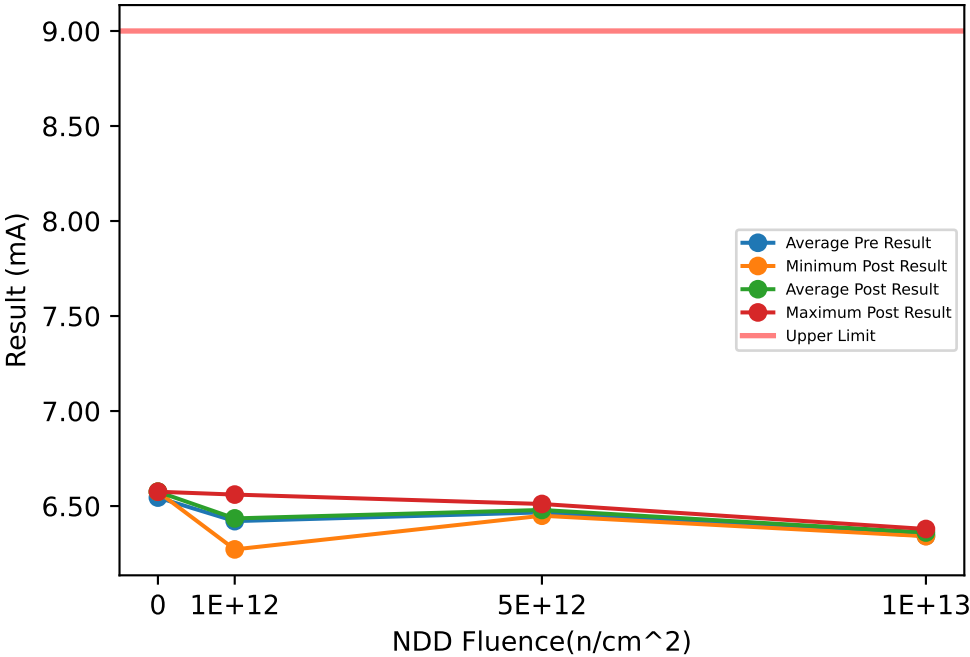


Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7786	3.7786	3.7786		3.8182	3.8182	3.8182		0.0396	0.0396	0.0396	
1e+12	3.5133	3.6183	3.6833	0.091766	3.5322	3.6333	3.693	0.088056	0.0097	0.015067	0.0189	0.0047878
5e+12	3.6724	3.7018	3.7262	0.027256	3.6881	3.7248	3.7447	0.031821	0.0157	0.022967	0.0347	0.010257
1e+13	3.5294	3.608	3.7551	0.12747	3.5558	3.6487	3.808	0.13862	0.0264	0.040633	0.0529	0.013359

Device Test: 36.6 I_OP_LS_PWM_500KHZ(Iop LS VIN PWM 500kHz VIN_12V)

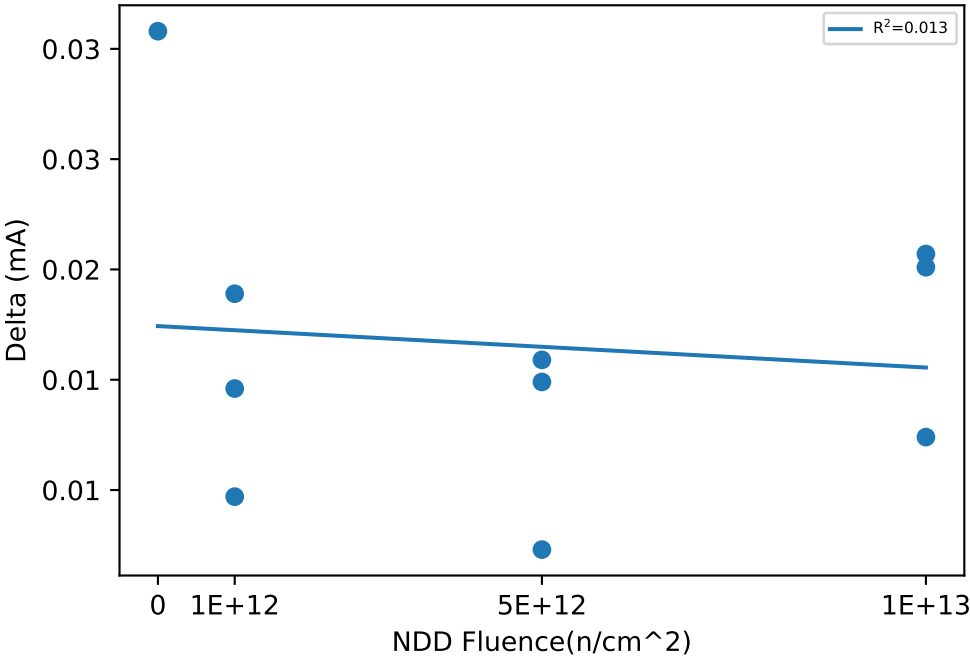
NDD vs Result Stats



Test Results (Upper Limit = 9.0 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	6.4582	6.4728	0.0146
551	1e+12	NDD	6.2622	6.2719	0.0097
552	1e+12	NDD	6.5415	6.5604	0.0189
553	5e+12	NDD	6.4634	6.4783	0.0149
554	5e+12	NDD	6.5036	6.5109	0.0073
555	5e+12	NDD	6.4332	6.4491	0.0159
556	1e+13	NDD	6.3414	6.3615	0.0201
557	1e+13	NDD	6.3586	6.3793	0.0207
558	1e+13	NDD	6.329	6.3414	0.0124
559	0	NDD, Ctrl	6.5446	6.5754	0.0308

NDD vs Post - Pre Exposure Delta

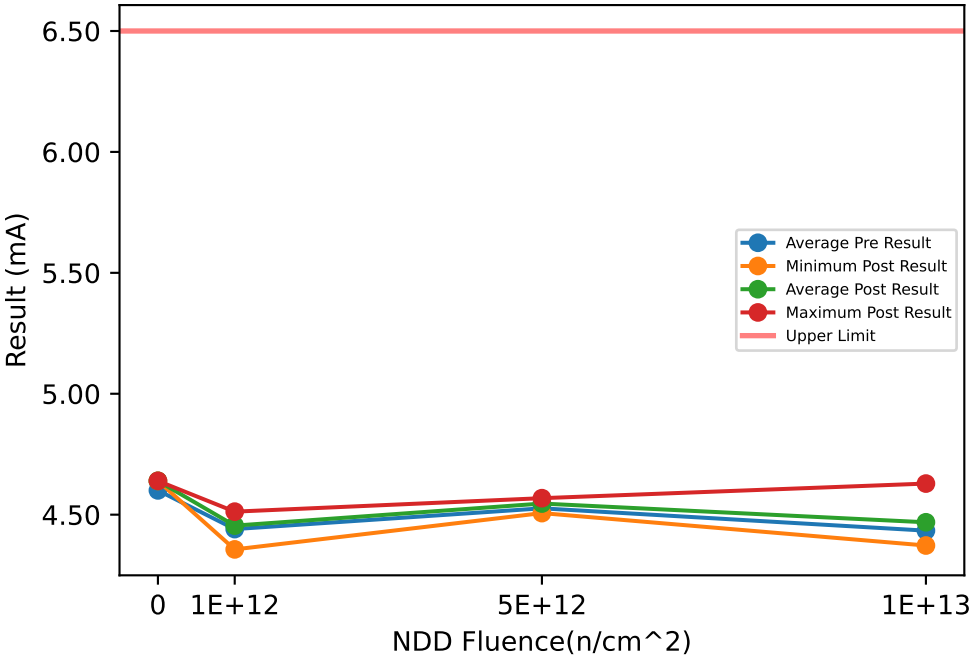


Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.5446	6.5446	6.5446		6.5754	6.5754	6.5754		0.0308	0.0308	0.0308	
1e+12	6.2622	6.4206	6.5415	0.14339	6.2719	6.435	6.5604	0.14791	0.0097	0.0144	0.0189	0.0046033
5e+12	6.4332	6.4667	6.5036	0.035318	6.4491	6.4794	6.5109	0.030916	0.0073	0.0127	0.0159	0.0047032
1e+13	6.329	6.343	6.3586	0.014865	6.3414	6.3607	6.3793	0.018962	0.0124	0.017733	0.0207	0.0046285

Device Test: 36.7 I_OP_HS_PWM_500KHZ(lop HS BOOT PWM 500kHz VIN_12V)

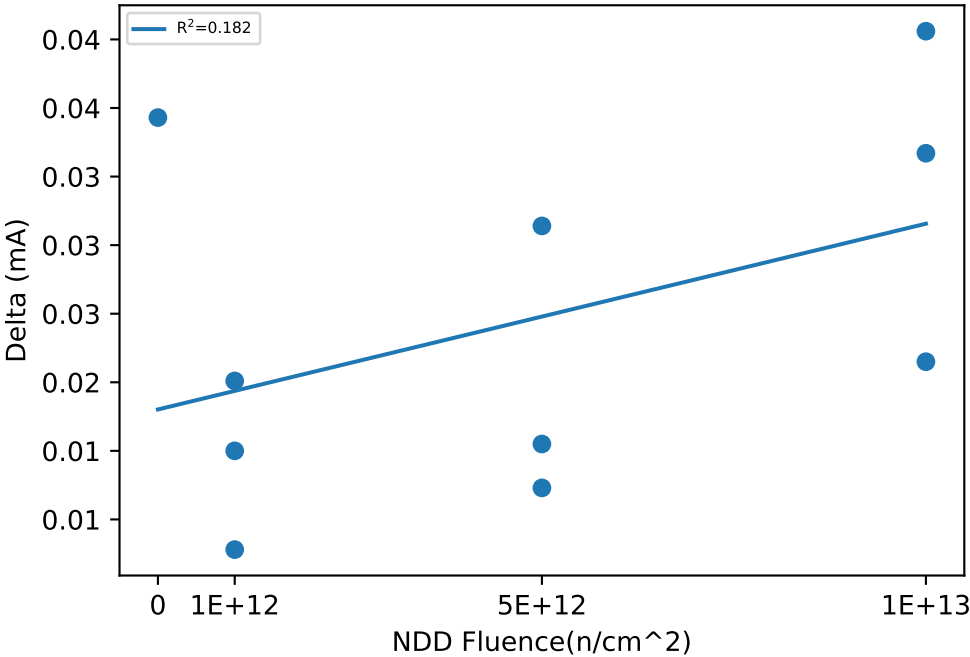
NDD vs Result Stats



Test Results (Upper Limit = 6.5 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.4802	4.4952	0.015
551	1e+12	NDD	4.3363	4.3564	0.0201
552	1e+12	NDD	4.5047	4.5125	0.0078
553	5e+12	NDD	4.5319	4.5633	0.0314
554	5e+12	NDD	4.5527	4.5682	0.0155
555	5e+12	NDD	4.4942	4.5065	0.0123
556	1e+13	NDD	4.351	4.3725	0.0215
557	1e+13	NDD	4.3678	4.4045	0.0367
558	1e+13	NDD	4.583	4.6286	0.0456
559	0	NDD, Ctrl	4.6004	4.6397	0.0393

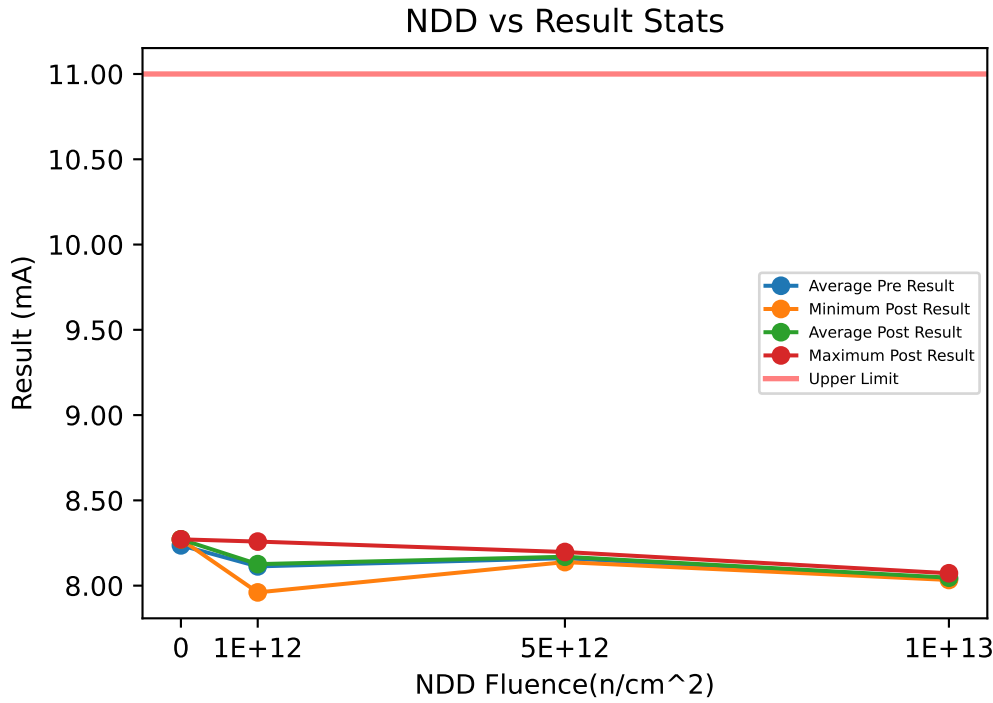
NDD vs Post - Pre Exposure Delta



Test Statistics (mA)

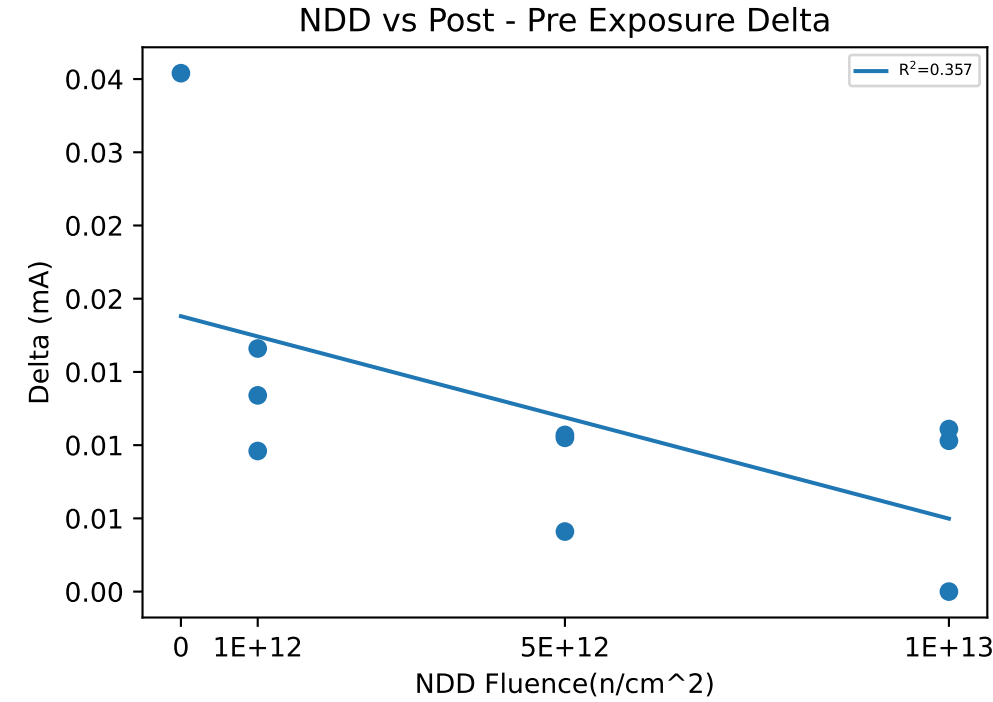
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.6004	4.6004	4.6004		4.6397	4.6397	4.6397		0.0393	0.0393	0.0393	
1e+12	4.3363	4.4404	4.5047	0.090982	4.3564	4.4547	4.5125	0.085569	0.0078	0.0143	0.0201	0.0061798
5e+12	4.4942	4.5263	4.5527	0.029654	4.5065	4.546	4.5682	0.034296	0.0123	0.019733	0.0314	0.01023
1e+13	4.351	4.4339	4.583	0.12937	4.3725	4.4685	4.6286	0.13954	0.0215	0.0346	0.0456	0.012186

Device Test: 36.8 I_OP_LS_PWM_1MHZ(Iop LS VIN PWM 1MHz VIN_12V)



Test Results (Upper Limit = 11.0 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	8.1461	8.1595	0.0134
551	1e+12	NDD	7.9508	7.9604	0.0096
552	1e+12	NDD	8.2418	8.2584	0.0166
553	5e+12	NDD	8.1625	8.173	0.0105
554	5e+12	NDD	8.1932	8.1973	0.0041
555	5e+12	NDD	8.1273	8.138	0.0107
556	1e+13	NDD	8.0231	8.0342	0.0111
557	1e+13	NDD	8.0623	8.0726	0.0103
558	1e+13	NDD	8.0332	8.0332	0
559	0	NDD, Ctrl	8.2362	8.2716	0.0354

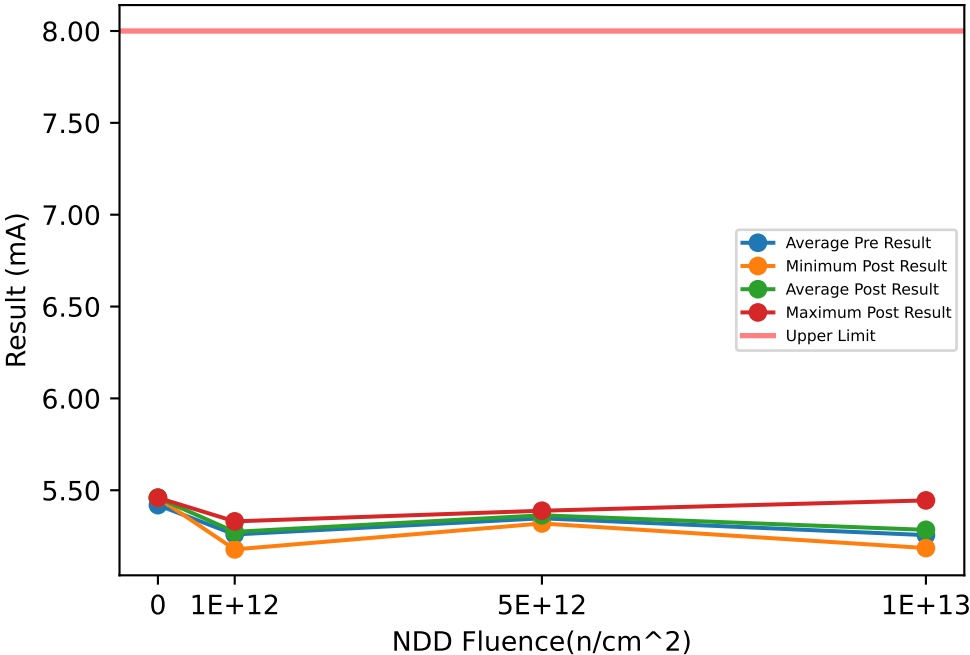


Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.2362	8.2362	8.2362		8.2716	8.2716	8.2716		0.0354	0.0354	0.0354	
1e+12	7.9508	8.1129	8.2418	0.14831	7.9604	8.1261	8.2584	0.15178	0.0096	0.0132	0.0166	0.0035043
5e+12	8.1273	8.161	8.1932	0.032976	8.138	8.1694	8.1973	0.02981	0.0041	0.0084333	0.0107	0.0037541
1e+13	8.0231	8.0395	8.0623	0.020353	8.0332	8.0467	8.0726	0.022464	0	0.0071333	0.0111	0.0061906

Device Test: 36.9 I_OP_HS_PWM_1MHZ(lop HS BOOT PWM 1MHz VIN_12V)

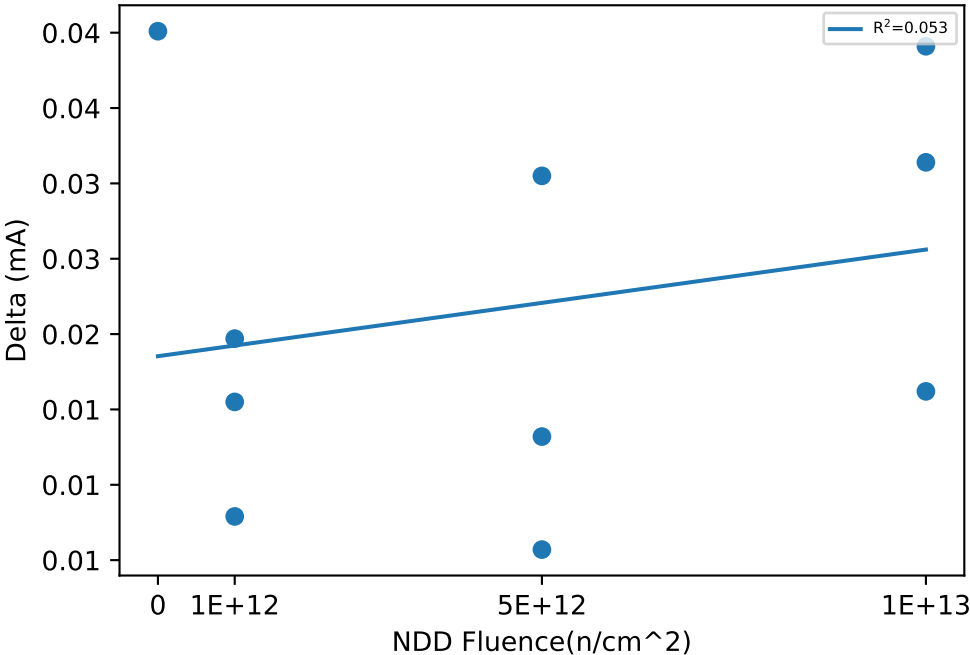
NDD vs Result Stats



Test Results (Upper Limit = 8.0 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	5.2967	5.3122	0.0155
551	1e+12	NDD	5.1583	5.178	0.0197
552	1e+12	NDD	5.3227	5.3306	0.0079
553	5e+12	NDD	5.3527	5.3832	0.0305
554	5e+12	NDD	5.3753	5.3885	0.0132
555	5e+12	NDD	5.3135	5.3192	0.0057
556	1e+13	NDD	5.169	5.1852	0.0162
557	1e+13	NDD	5.1923	5.2237	0.0314
558	1e+13	NDD	5.4056	5.4447	0.0391
559	0	NDD, Ctrl	5.419	5.4591	0.0401

NDD vs Post - Pre Exposure Delta

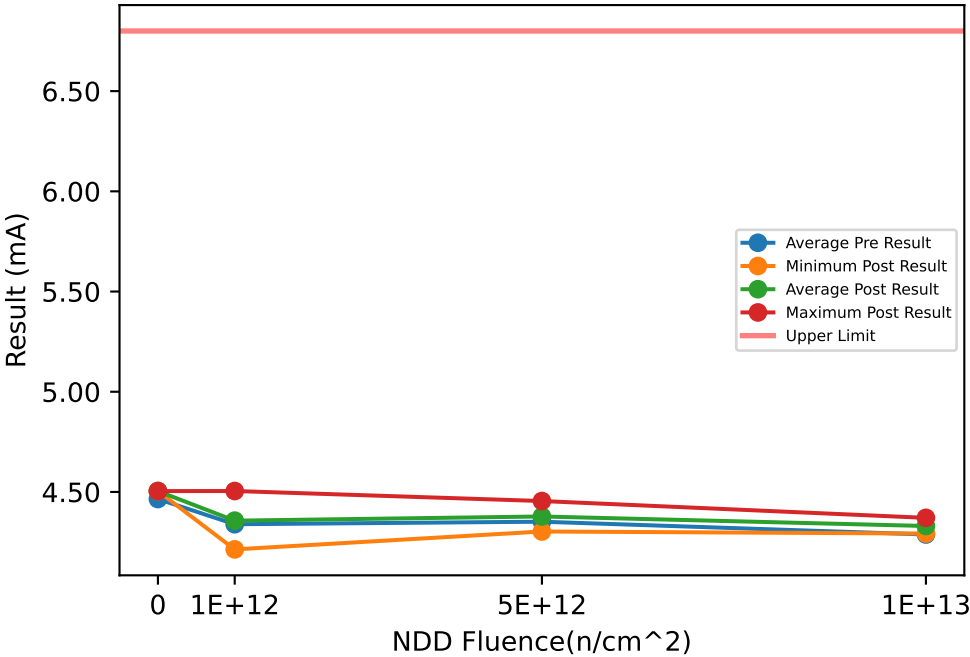


Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.419	5.419	5.419		5.4591	5.4591	5.4591		0.0401	0.0401	0.0401	
1e+12	5.1583	5.2592	5.3227	0.088372	5.178	5.2736	5.3306	0.083302	0.0079	0.014367	0.0197	0.0059811
5e+12	5.3135	5.3472	5.3753	0.031269	5.3192	5.3636	5.3885	0.038572	0.0057	0.016467	0.0305	0.012719
1e+13	5.169	5.2556	5.4056	0.1304	5.1852	5.2845	5.4447	0.14004	0.0162	0.0289	0.0391	0.011653

Device Test: 37.0 IQ_LS_PWM(Iq LS VIN PWM VIN_14V)

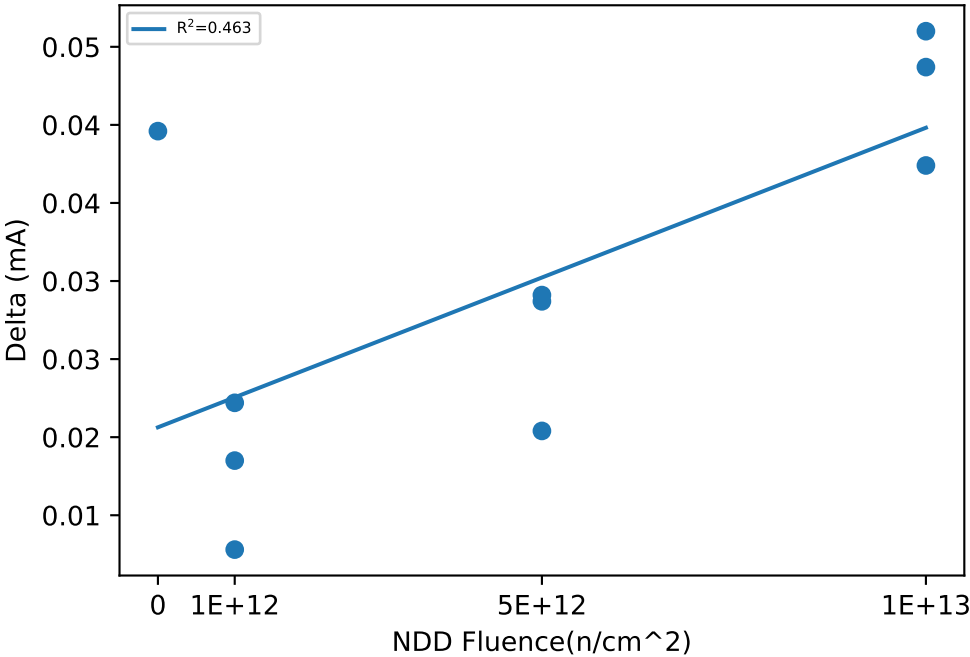
NDD vs Result Stats



Test Results (Upper Limit = 6.8 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.3338	4.3523	0.0185
551	1e+12	NDD	4.2006	4.2134	0.0128
552	1e+12	NDD	4.4825	4.5047	0.0222
553	5e+12	NDD	4.3465	4.3756	0.0291
554	5e+12	NDD	4.4343	4.4547	0.0204
555	5e+12	NDD	4.274	4.3027	0.0287
556	1e+13	NDD	4.2812	4.3272	0.046
557	1e+13	NDD	4.2488	4.2925	0.0437
558	1e+13	NDD	4.3334	4.3708	0.0374
559	0	NDD, Ctrl	4.4647	4.5043	0.0396

NDD vs Post - Pre Exposure Delta

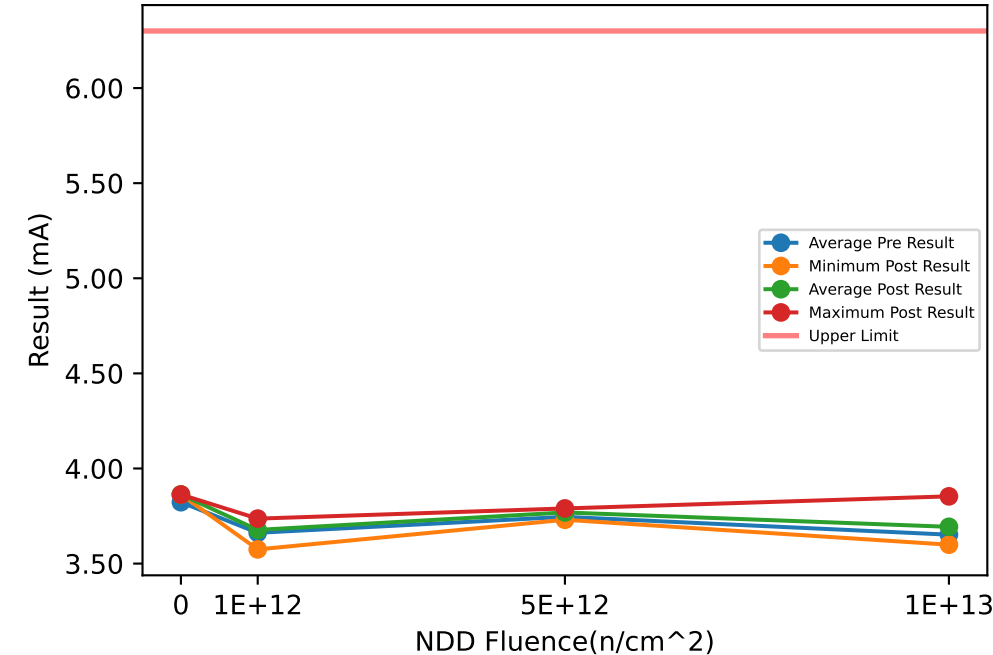


Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.4647	4.4647	4.4647		4.5043	4.5043	4.5043		0.0396	0.0396	0.0396	
1e+12	4.2006	4.339	4.4825	0.14102	4.2134	4.3568	4.5047	0.1457	0.0128	0.017833	0.0222	0.0047353
5e+12	4.274	4.3516	4.4343	0.080272	4.3027	4.3777	4.4547	0.076021	0.0204	0.026067	0.0291	0.0049116
1e+13	4.2488	4.2878	4.3334	0.042684	4.2925	4.3302	4.3708	0.039234	0.0374	0.042367	0.046	0.0044523

Device Test: 37.1 IQ_HS_PWM(Iq HS BOOT PWM VIN_14V)

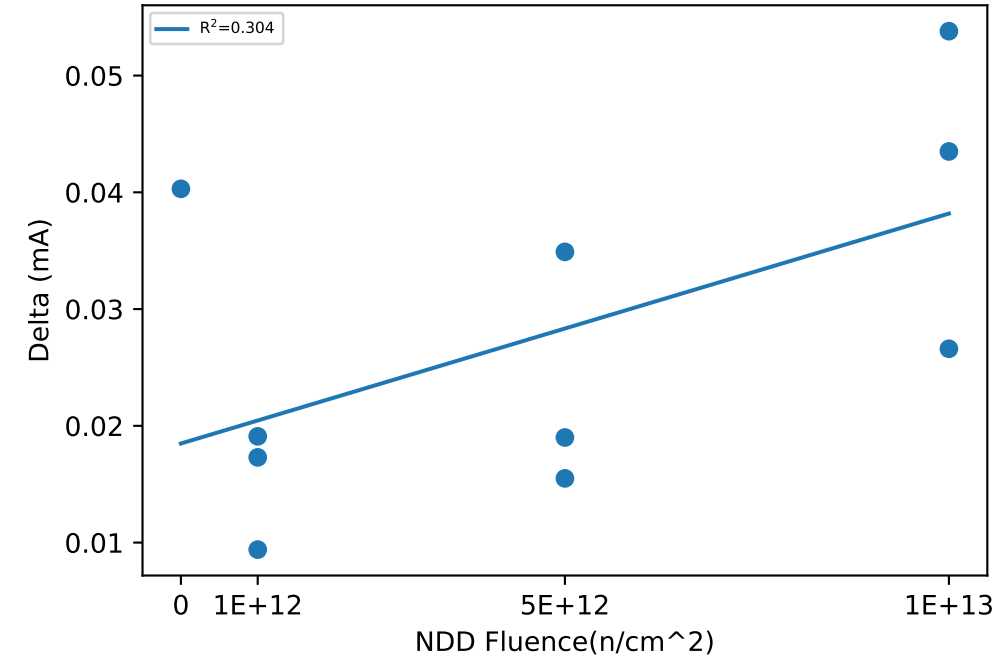
NDD vs Result Stats



Test Results (Upper Limit = 6.3 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	3.7031	3.7204	0.0173
551	1e+12	NDD	3.5555	3.5746	0.0191
552	1e+12	NDD	3.727	3.7364	0.0094
553	5e+12	NDD	3.7513	3.7862	0.0349
554	5e+12	NDD	3.7709	3.7899	0.019
555	5e+12	NDD	3.7149	3.7304	0.0155
556	1e+13	NDD	3.5727	3.5993	0.0266
557	1e+13	NDD	3.5837	3.6272	0.0435
558	1e+13	NDD	3.7997	3.8535	0.0538
559	0	NDD, Ctrl	3.8227	3.863	0.0403

NDD vs Post - Pre Exposure Delta

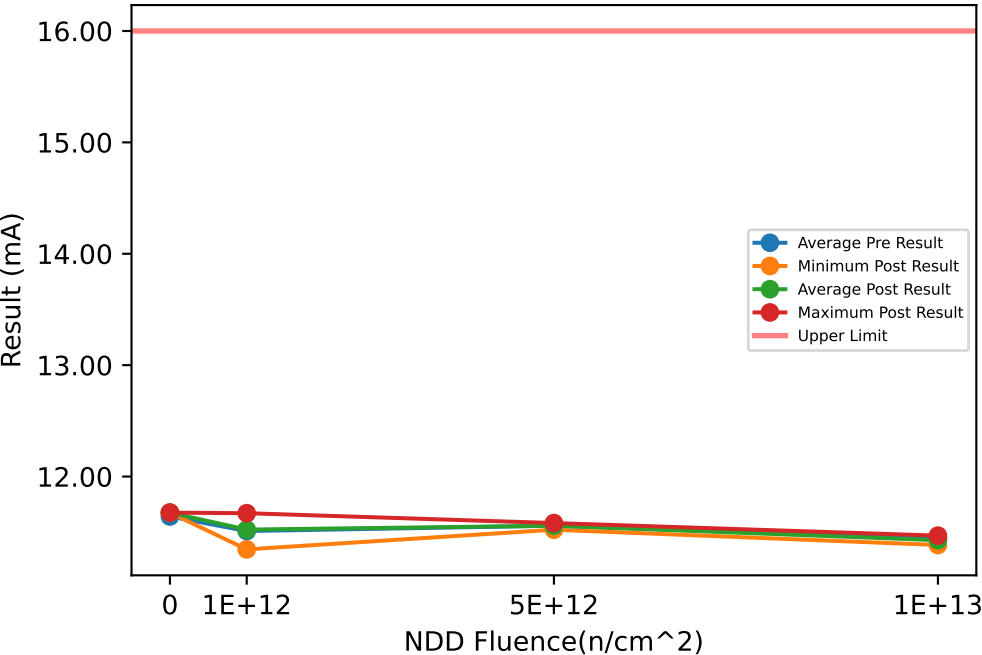


Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.8227	3.8227	3.8227		3.863	3.863	3.863		0.0403	0.0403	0.0403	
1e+12	3.5555	3.6619	3.727	0.092888	3.5746	3.6771	3.7364	0.089156	0.0094	0.015267	0.0191	0.0051598
5e+12	3.7149	3.7457	3.7709	0.028417	3.7304	3.7688	3.7899	0.033336	0.0155	0.023133	0.0349	0.010339
1e+13	3.5727	3.652	3.7997	0.128	3.5993	3.6933	3.8535	0.13941	0.0266	0.0413	0.0538	0.013733

Device Test: 37.10 I_OP_LS_PWM_2MHZ(lop LS VIN PWM 2MHz VIN_14V)

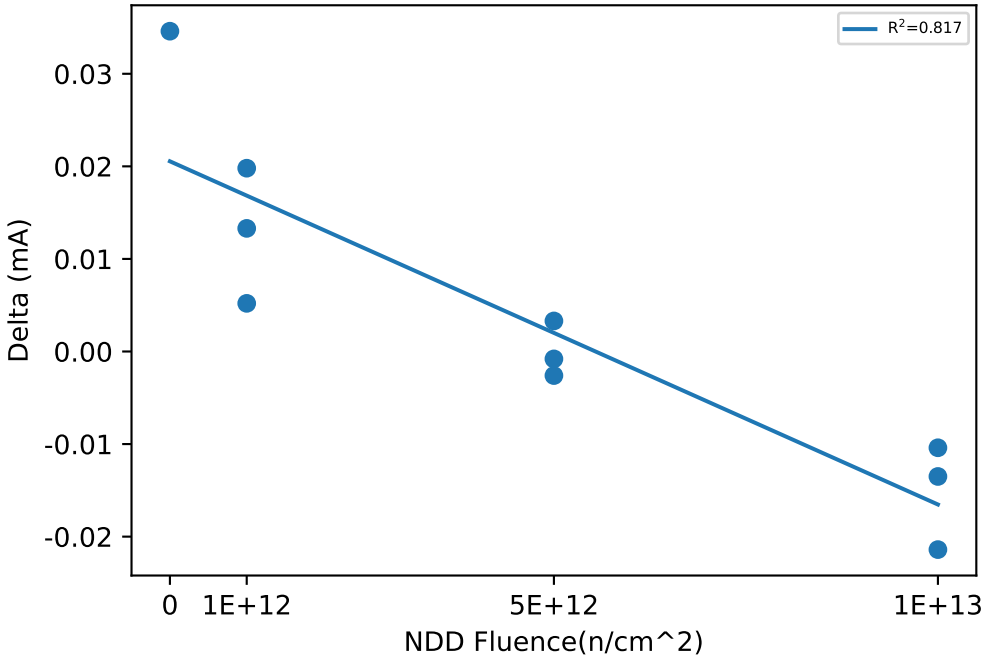
NDD vs Result Stats



Test Results (Upper Limit = 16.0 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	11.549	11.554	0.0052
551	1e+12	NDD	11.332	11.346	0.0133
552	1e+12	NDD	11.651	11.671	0.0198
553	5e+12	NDD	11.567	11.57	0.0033
554	5e+12	NDD	11.585	11.582	-0.0026
555	5e+12	NDD	11.523	11.523	-0.0008
556	1e+13	NDD	11.399	11.385	-0.0135
557	1e+13	NDD	11.48	11.469	-0.0104
558	1e+13	NDD	11.452	11.431	-0.0214
559	0	NDD, Ctrl	11.641	11.676	0.0346

NDD vs Post - Pre Exposure Delta

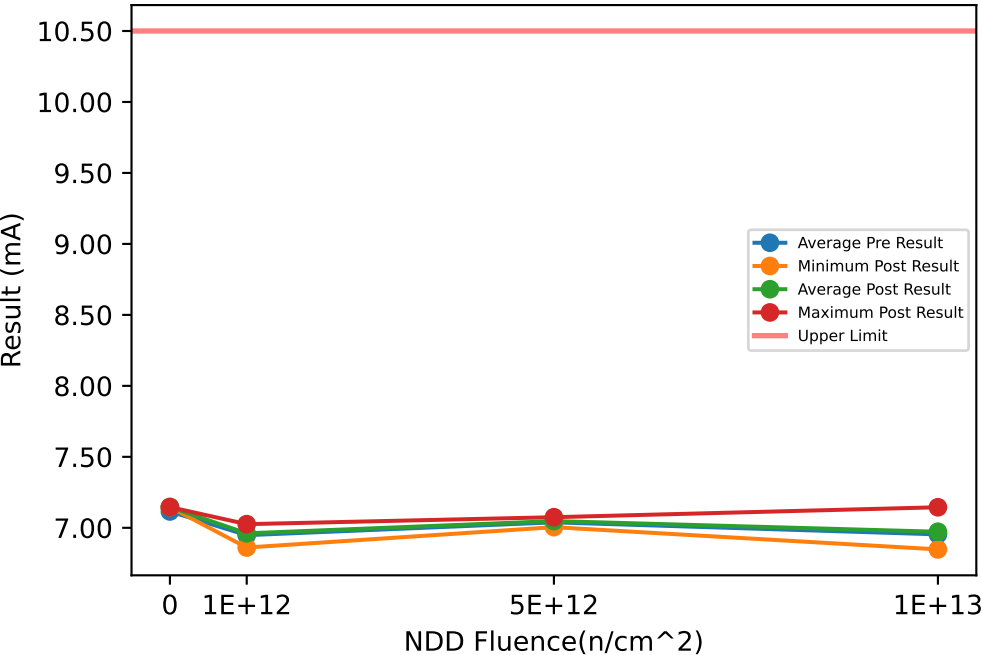


Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	11.641	11.641	11.641		11.676	11.676	11.676		0.0346	0.0346	0.0346	
1e+12	11.332	11.511	11.651	0.16262	11.346	11.524	11.671	0.16463	0.0052	0.012767	0.0198	0.0073146
5e+12	11.523	11.558	11.585	0.031619	11.523	11.558	11.582	0.03156	-0.0026	-3.3333e-05	0.0033	0.0030238
1e+13	11.399	11.444	11.48	0.041026	11.385	11.428	11.469	0.041946	-0.0214	-0.0151	-0.0104	0.0056719

Device Test: 37.11 I_OP_HS_PWM_2MHZ(Iop HS BOOT PWM 2MHz VIN_14V)

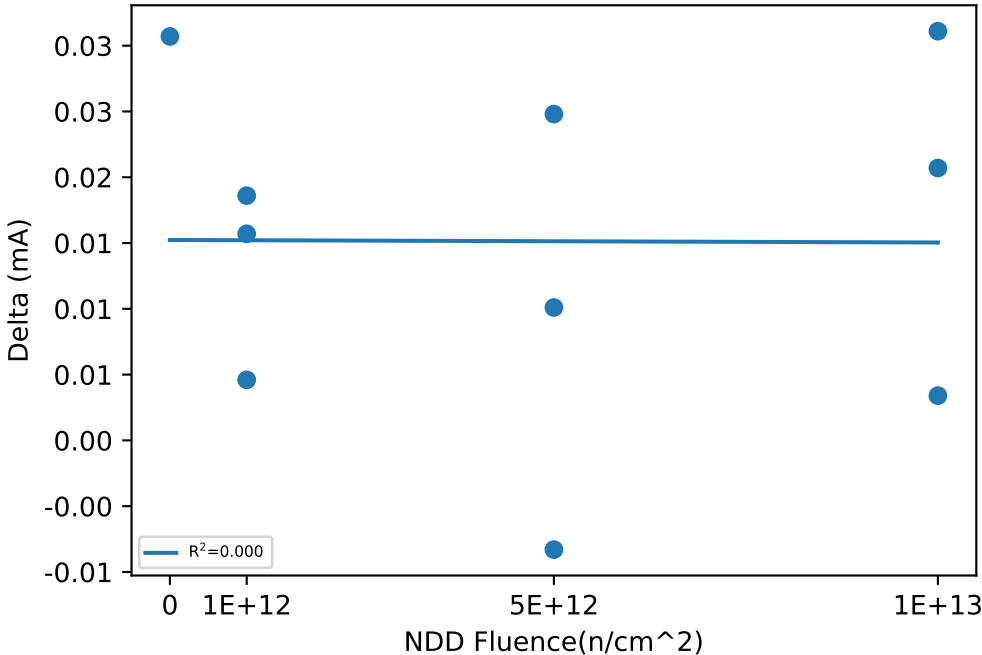
NDD vs Result Stats



Test Results (Upper Limit = 10.5 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	6.9807	6.9964	0.0157
551	1e+12	NDD	6.8424	6.861	0.0186
552	1e+12	NDD	7.0211	7.0257	0.0046
553	5e+12	NDD	7.0499	7.0747	0.0248
554	5e+12	NDD	7.0527	7.0628	0.0101
555	5e+12	NDD	7.0129	7.0046	-0.0083
556	1e+13	NDD	6.8445	6.8479	0.0034
557	1e+13	NDD	6.9032	6.9239	0.0207
558	1e+13	NDD	7.1136	7.1447	0.0311
559	0	NDD, Ctrl	7.1152	7.1459	0.0307

NDD vs Post - Pre Exposure Delta

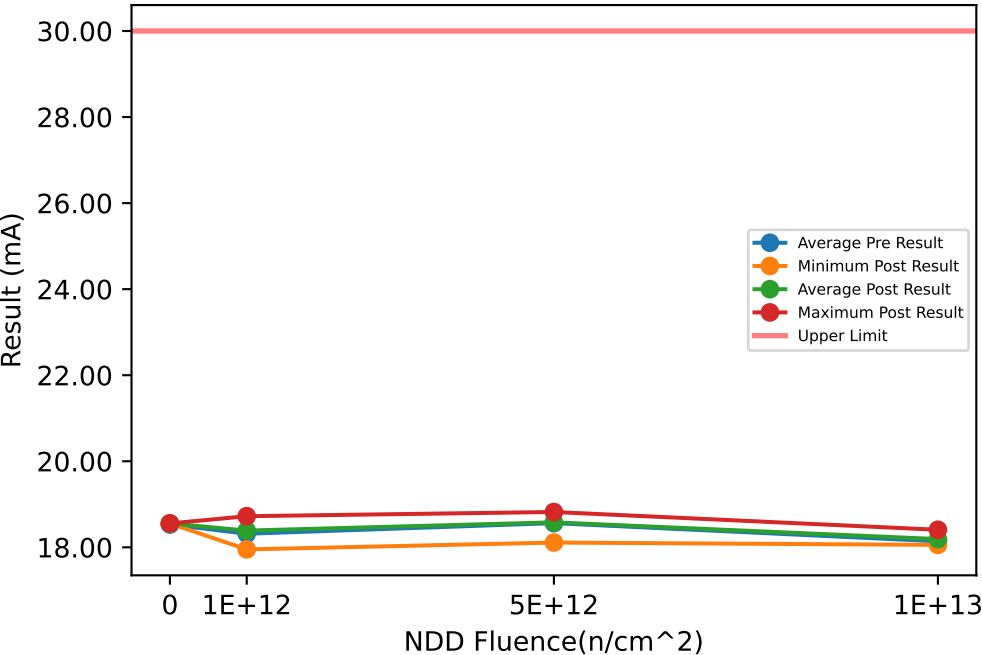


Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.1152	7.1152	7.1152		7.1459	7.1459	7.1459		0.0307	0.0307	0.0307	
1e+12	6.8424	6.9481	7.0211	0.093713	6.861	6.961	7.0257	0.087861	0.0046	0.012967	0.0186	0.0073894
5e+12	7.0129	7.0385	7.0527	0.022214	7.0046	7.0474	7.0747	0.037512	-0.0083	0.0088667	0.0248	0.016584
1e+13	6.8445	6.9538	7.1136	0.1415	6.8479	6.9722	7.1447	0.15417	0.0034	0.0184	0.0311	0.013992

Device Test: 37.12 I_OP_LS_PWM_5MHZ(lop LS VIN PWM 5MHz VIN_14V)

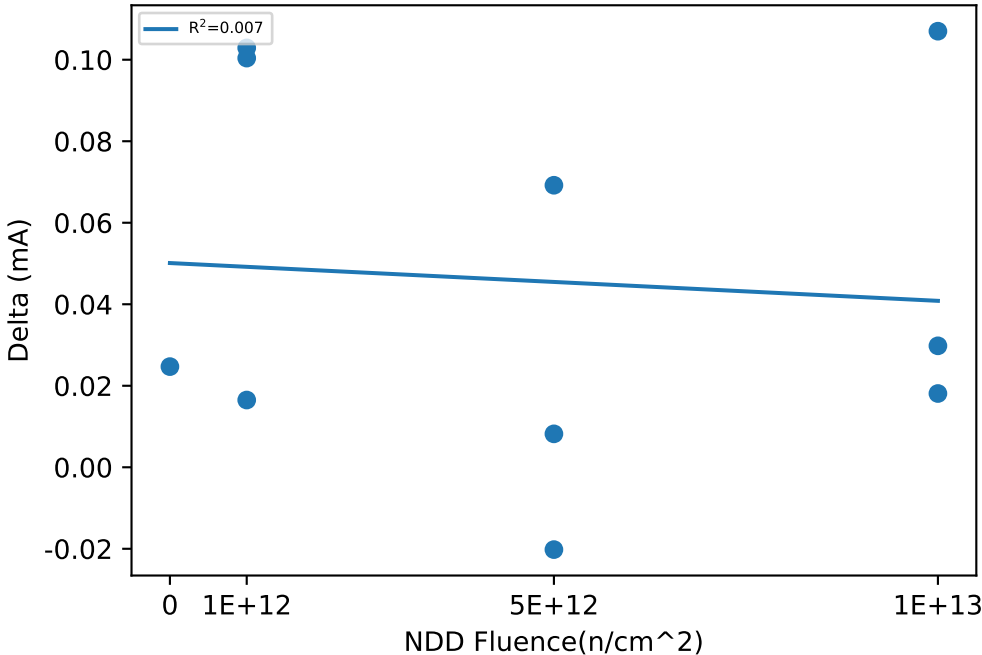
NDD vs Result Stats



Test Results (Upper Limit = 30.0 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	18.389	18.491	0.1029
551	1e+12	NDD	17.935	17.952	0.0165
552	1e+12	NDD	18.623	18.723	0.1004
553	5e+12	NDD	18.802	18.81	0.0082
554	5e+12	NDD	18.841	18.821	-0.0202
555	5e+12	NDD	18.042	18.111	0.0692
556	1e+13	NDD	18.39	18.408	0.0181
557	1e+13	NDD	18.004	18.111	0.107
558	1e+13	NDD	18.027	18.057	0.0298
559	0	NDD, Ctrl	18.53	18.555	0.0247

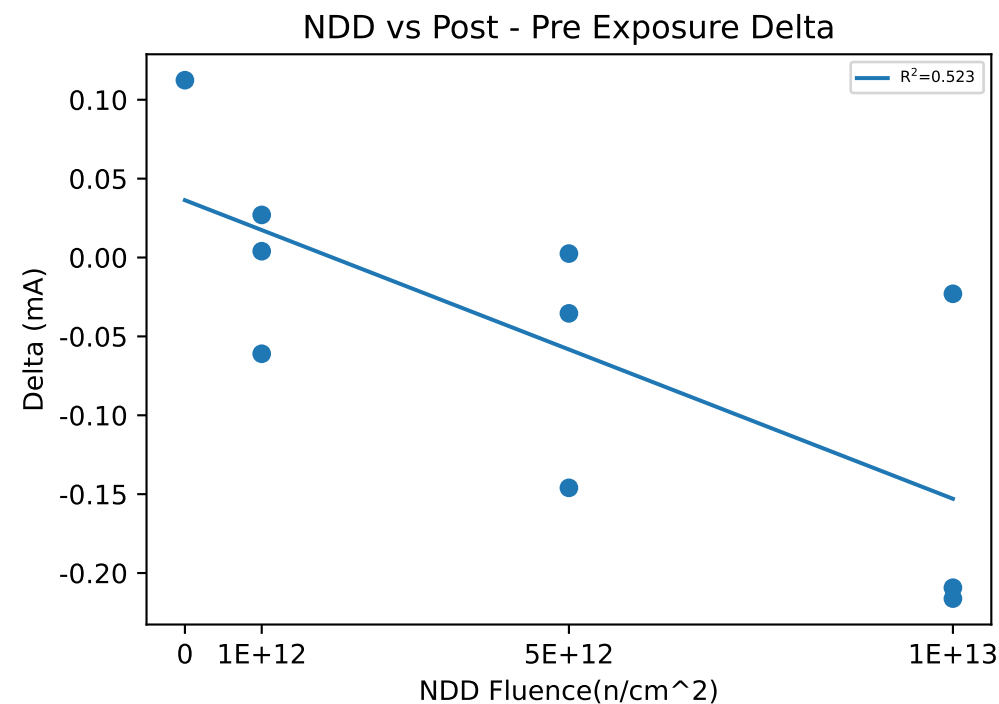
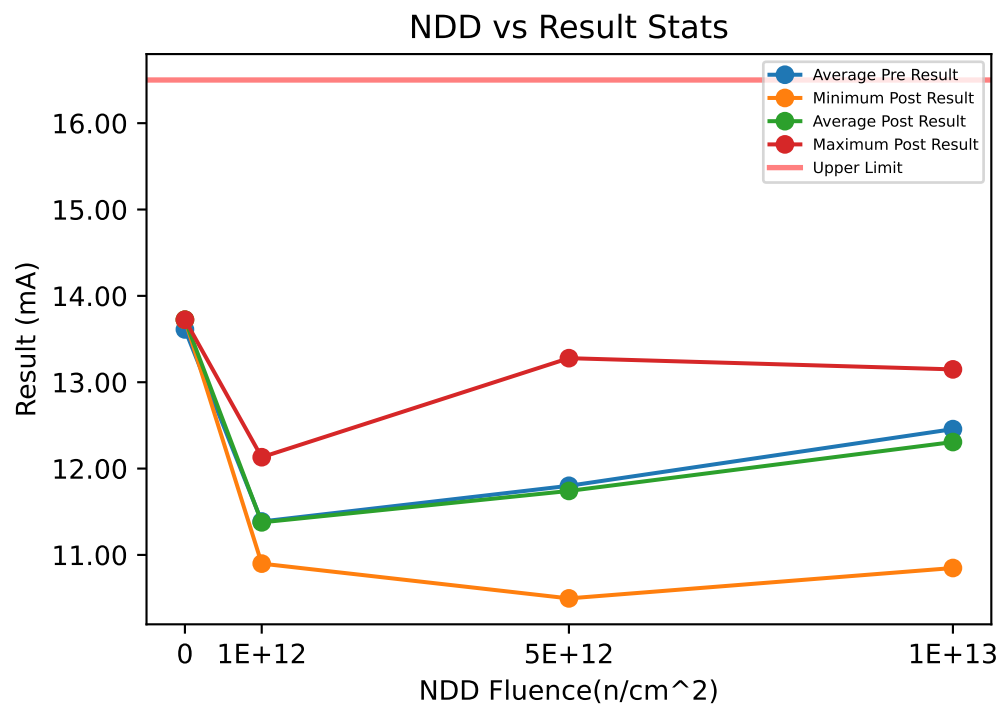
NDD vs Post - Pre Exposure Delta



Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	18.53	18.53	18.53		18.555	18.555	18.555		0.0247	0.0247	0.0247	
1e+12	17.935	18.315	18.623	0.34957	17.952	18.389	18.723	0.39587	0.0165	0.073267	0.1029	0.049177
5e+12	18.042	18.562	18.841	0.45081	18.111	18.581	18.821	0.40701	-0.0202	0.019067	0.0692	0.04568
1e+13	18.004	18.14	18.39	0.21641	18.057	18.192	18.408	0.189	0.0181	0.051633	0.107	0.048304

Device Test: 37.13 I_OP_HS_PWM_5MHZ(Iop HS BOOT PWM 5MHz VIN_14V)



Test Results (Upper Limit = 16.5 (mA))

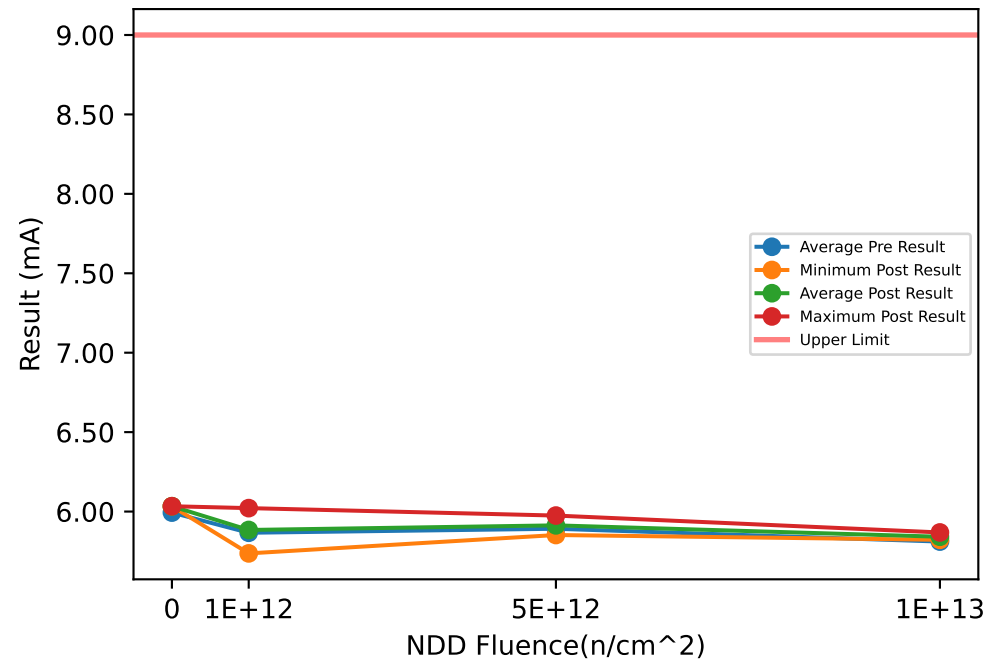
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	11.074	11.101	0.027
551	1e+12	NDD	10.895	10.899	0.004
552	1e+12	NDD	12.193	12.132	-0.061
553	5e+12	NDD	11.483	11.448	-0.0354
554	5e+12	NDD	10.494	10.496	0.0025
555	5e+12	NDD	13.425	13.278	-0.146
556	1e+13	NDD	10.871	10.848	-0.023
557	1e+13	NDD	13.358	13.149	-0.2093
558	1e+13	NDD	13.141	12.925	-0.2162
559	0	NDD, Ctrl	13.611	13.724	0.1124

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	13.611	13.611	13.611		13.724	13.724	13.724		0.1124	0.1124	0.1124	
1e+12	10.895	11.387	12.193	0.70308	10.899	11.377	12.132	0.66095	-0.061	-0.01	0.027	0.04564
5e+12	10.494	11.8	13.425	1.4908	10.496	11.741	13.278	1.414	-0.146	-0.059633	0.0025	0.077159
1e+13	10.871	12.457	13.358	1.3772	10.848	12.307	13.149	1.2683	-0.2162	-0.1495	-0.023	0.10961

Device Test: 37.14 I_OP_LS_IIM_500KHZ_INTERLOCK(Iop LS VIN IIM Interlock 500kHz VIN_14V)

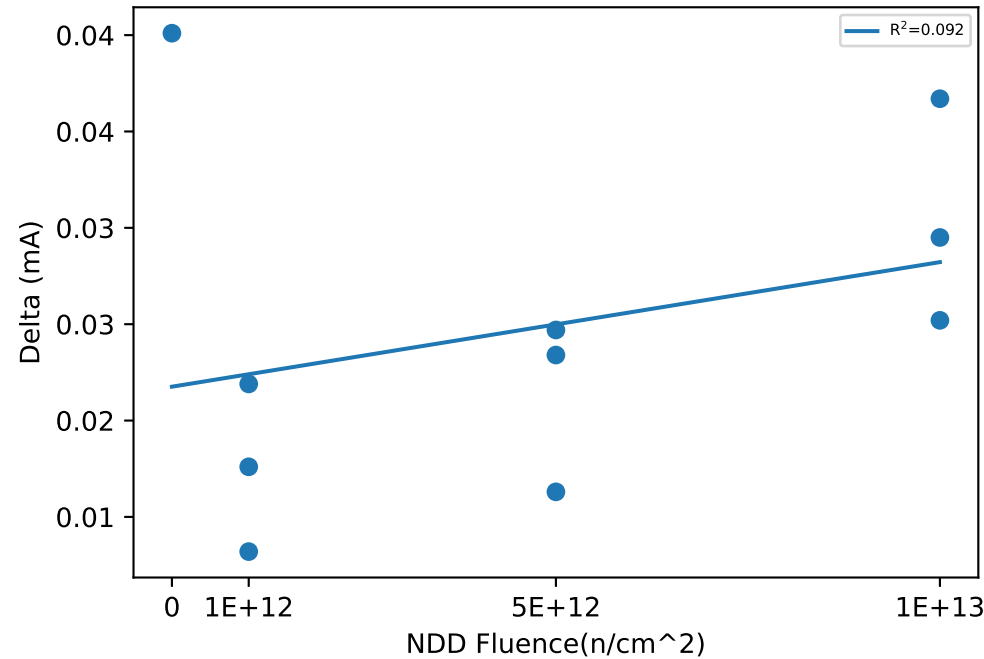
NDD vs Result Stats



Test Results (Upper Limit = 9.0 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	5.8765	5.8941	0.0176
551	1e+12	NDD	5.7234	5.7366	0.0132
552	1e+12	NDD	5.9997	6.0216	0.0219
553	5e+12	NDD	5.8876	5.9123	0.0247
554	5e+12	NDD	5.9585	5.9748	0.0163
555	5e+12	NDD	5.8289	5.8523	0.0234
556	1e+13	NDD	5.7971	5.8338	0.0367
557	1e+13	NDD	5.7925	5.822	0.0295
558	1e+13	NDD	5.8433	5.8685	0.0252
559	0	NDD, Ctrl	5.9934	6.0335	0.0401

NDD vs Post - Pre Exposure Delta

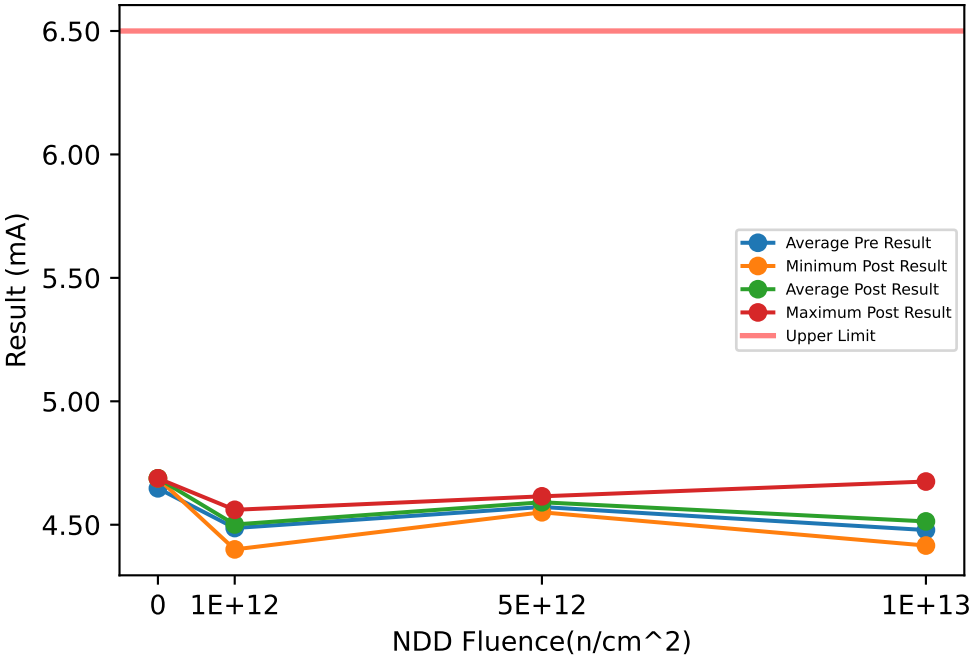


Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.9934	5.9934	5.9934		6.0335	6.0335	6.0335		0.0401	0.0401	0.0401	
1e+12	5.7234	5.8665	5.9997	0.13842	5.7366	5.8841	6.0216	0.14276	0.0132	0.017567	0.0219	0.0043501
5e+12	5.8289	5.8917	5.9585	0.064896	5.8523	5.9131	5.9748	0.061254	0.0163	0.021467	0.0247	0.0045214
1e+13	5.7925	5.811	5.8433	0.028096	5.822	5.8414	5.8685	0.024172	0.0252	0.030467	0.0367	0.0058106

Device Test: 37.15 I_OP_HS_IIM_500KHZ_INTERLOCK(Iop HS BOOT IIM Interlock 500kHz VIN_14V)

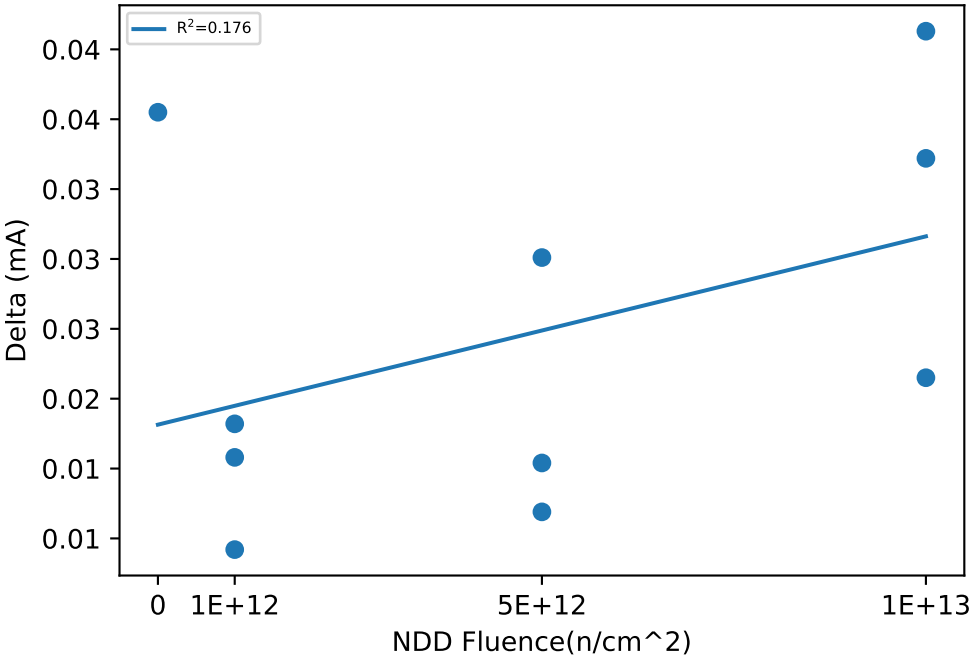
NDD vs Result Stats



Test Results (Upper Limit = 6.5 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.5267	4.5425	0.0158
551	1e+12	NDD	4.3819	4.4001	0.0182
552	1e+12	NDD	4.5513	4.5605	0.0092
553	5e+12	NDD	4.5775	4.6076	0.0301
554	5e+12	NDD	4.5997	4.6151	0.0154
555	5e+12	NDD	4.5385	4.5504	0.0119
556	1e+13	NDD	4.3942	4.4157	0.0215
557	1e+13	NDD	4.4125	4.4497	0.0372
558	1e+13	NDD	4.6287	4.675	0.0463
559	0	NDD, Ctrl	4.6475	4.688	0.0405

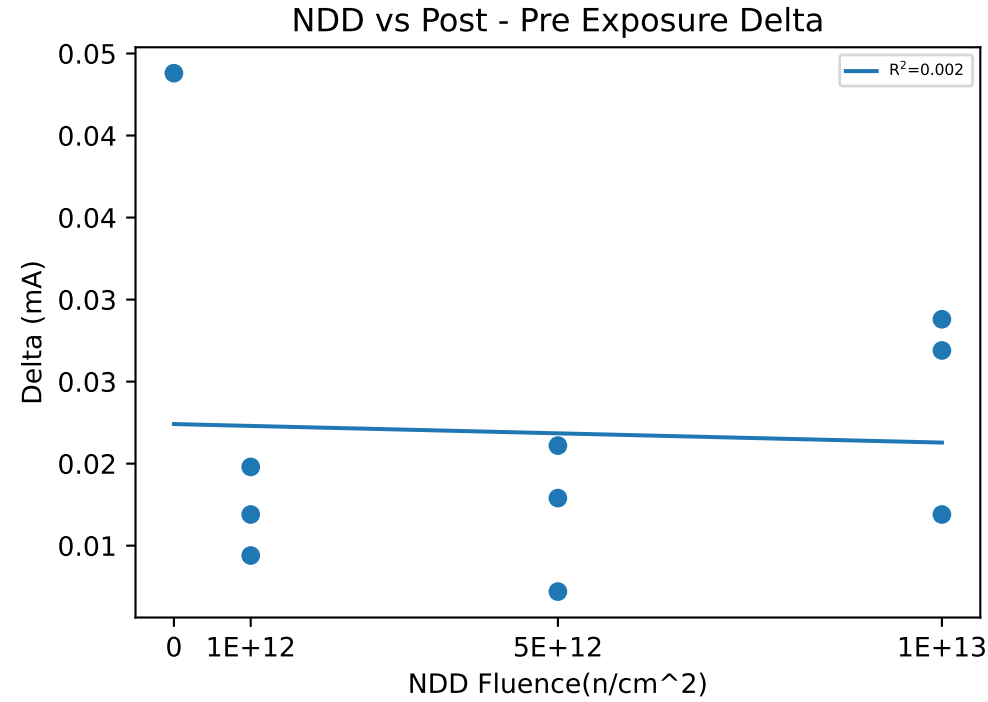
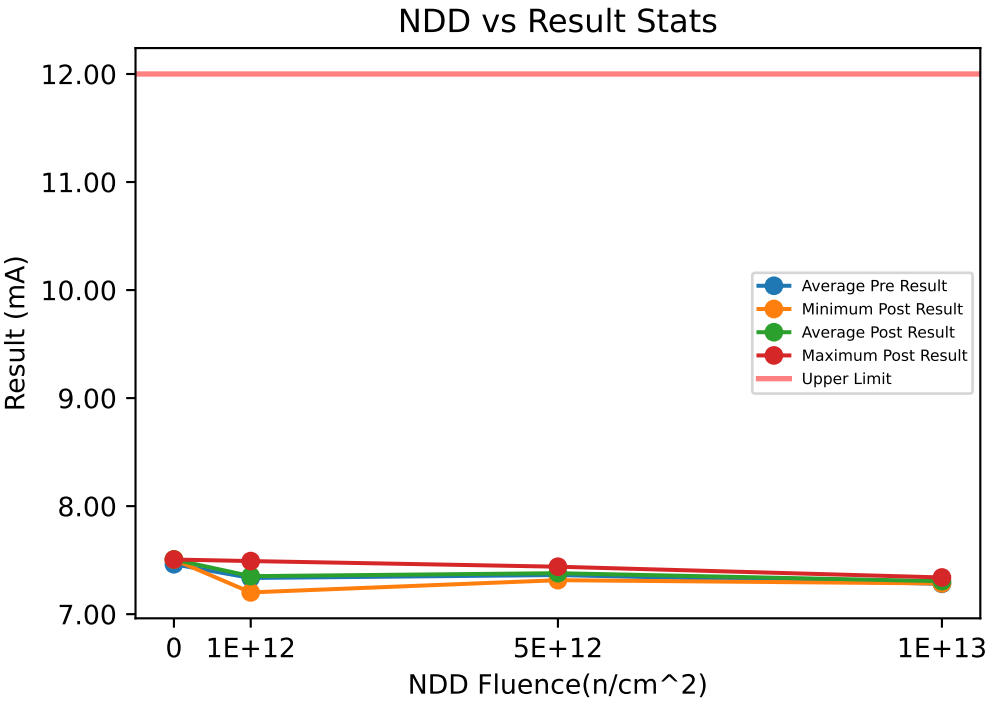
NDD vs Post - Pre Exposure Delta



Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.6475	4.6475	4.6475		4.688	4.688	4.688		0.0405	0.0405	0.0405	
1e+12	4.3819	4.4866	4.5513	0.091532	4.4001	4.501	4.5605	0.087873	0.0092	0.0144	0.0182	0.0046605
5e+12	4.5385	4.5719	4.5997	0.030982	4.5504	4.591	4.6151	0.035389	0.0119	0.019133	0.0301	0.0096573
1e+13	4.3942	4.4785	4.6287	0.13043	4.4157	4.5135	4.675	0.14092	0.0215	0.035	0.0463	0.012546

Device Test: 37.16 I_OP_LS_IIM_1MHZ_INTERLOCK(Iop LS VIN IIM Interlock 1MHz VIN_14V)



Test Results (Upper Limit = 12.0 (mA))

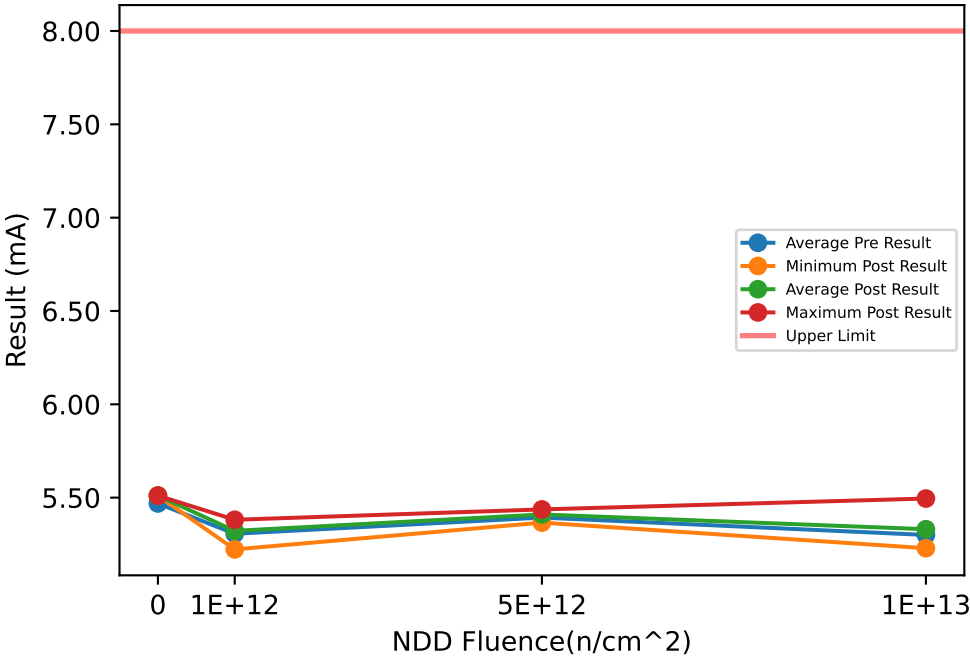
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	7.3458	7.3627	0.0169
551	1e+12	NDD	7.1871	7.2015	0.0144
552	1e+12	NDD	7.4717	7.4915	0.0198
553	5e+12	NDD	7.3626	7.3837	0.0211
554	5e+12	NDD	7.4271	7.4393	0.0122
555	5e+12	NDD	7.2967	7.3146	0.0179
556	1e+13	NDD	7.2553	7.2841	0.0288
557	1e+13	NDD	7.2648	7.2917	0.0269
558	1e+13	NDD	7.3228	7.3397	0.0169
559	0	NDD, Ctrl	7.462	7.5058	0.0438

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.462	7.462	7.462		7.5058	7.5058	7.5058		0.0438	0.0438	0.0438	
1e+12	7.1871	7.3349	7.4717	0.14261	7.2015	7.3519	7.4915	0.1453	0.0144	0.017033	0.0198	0.0027025
5e+12	7.2967	7.3621	7.4271	0.065201	7.3146	7.3792	7.4393	0.062472	0.0122	0.017067	0.0211	0.0045081
1e+13	7.2553	7.281	7.3228	0.036539	7.2841	7.3052	7.3397	0.030147	0.0169	0.0242	0.0288	0.006393

Device Test: 37.17 I_OP_HS_IIM_1MHZ_INTERLOCK(Iop HS BOOT IIM Interlock 1MHz VIN_14V)

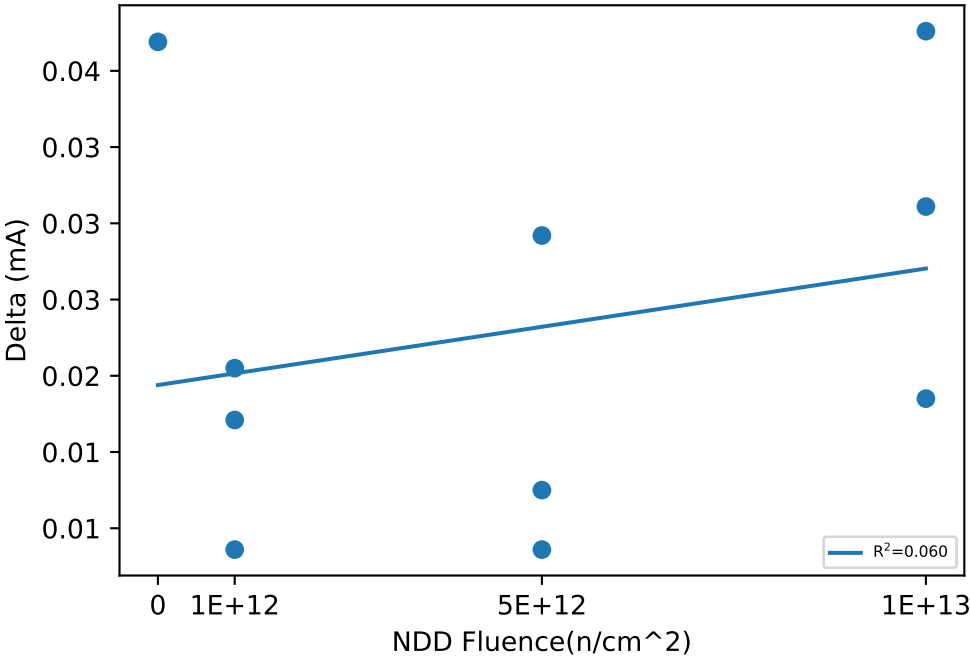
NDD vs Result Stats



Test Results (Upper Limit = 8.0 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	5.3446	5.3617	0.0171
551	1e+12	NDD	5.2022	5.2227	0.0205
552	1e+12	NDD	5.3729	5.3815	0.0086
553	5e+12	NDD	5.3976	5.4268	0.0292
554	5e+12	NDD	5.4244	5.4369	0.0125
555	5e+12	NDD	5.3575	5.3661	0.0086
556	1e+13	NDD	5.2106	5.2291	0.0185
557	1e+13	NDD	5.2372	5.2683	0.0311
558	1e+13	NDD	5.4526	5.4952	0.0426
559	0	NDD, Ctrl	5.4689	5.5108	0.0419

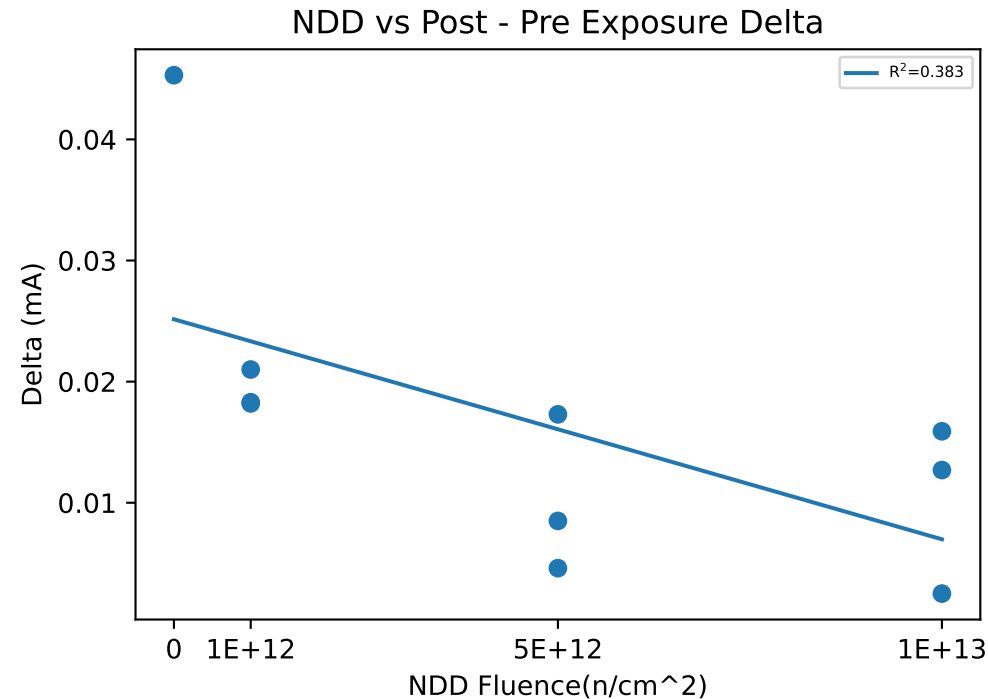
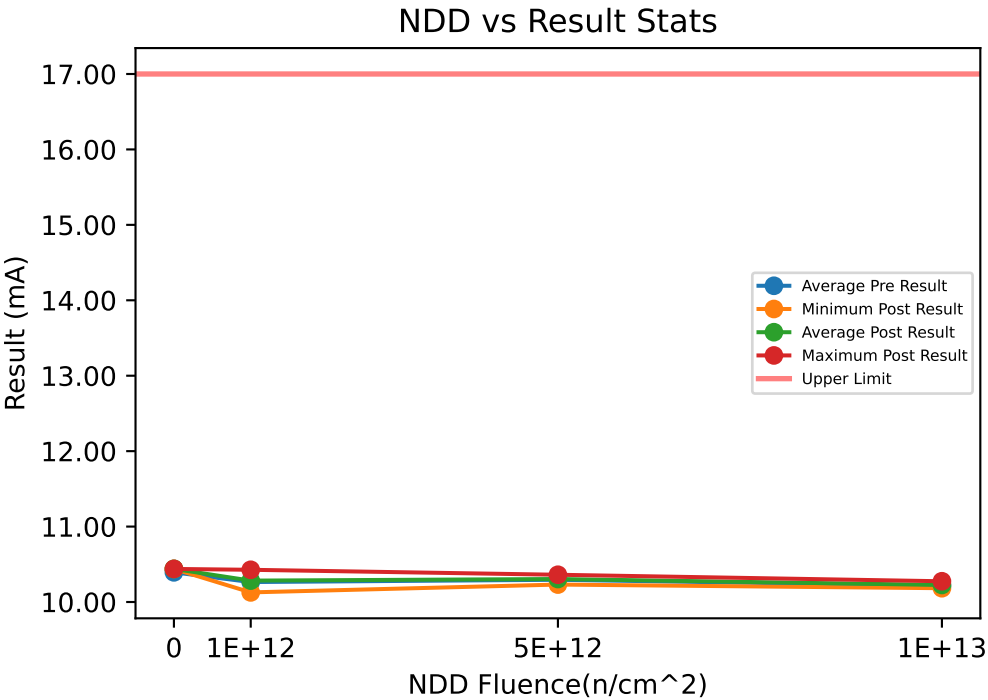
NDD vs Post - Pre Exposure Delta



Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.4689	5.4689	5.4689		5.5108	5.5108	5.5108		0.0419	0.0419	0.0419	
1e+12	5.2022	5.3066	5.3729	0.091485	5.2227	5.322	5.3815	0.086536	0.0086	0.0154	0.0205	0.0061294
5e+12	5.3575	5.3932	5.4244	0.03367	5.3661	5.4099	5.4369	0.038295	0.0086	0.016767	0.0292	0.010943
1e+13	5.2106	5.3001	5.4526	0.13271	5.2291	5.3309	5.4952	0.14366	0.0185	0.030733	0.0426	0.012054

Device Test: 37.18 I_OP_LS_IIM_2MHZ_INTERLOCK(Iop LS VIN IIM Interlock 2MHz VIN_14V)

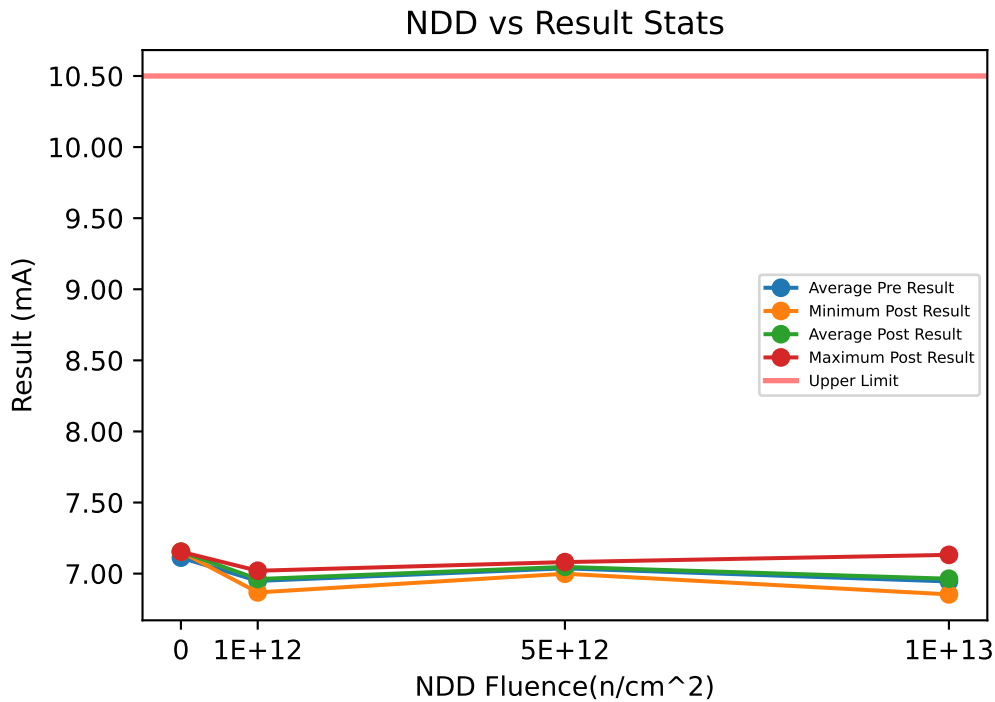


Test Results (Upper Limit = 17.0 (mA))					
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	10.278	10.297	0.0183
551	1e+12	NDD	10.109	10.127	0.0182
552	1e+12	NDD	10.406	10.427	0.021
553	5e+12	NDD	10.304	10.322	0.0173
554	5e+12	NDD	10.357	10.361	0.0046
555	5e+12	NDD	10.223	10.231	0.0085
556	1e+13	NDD	10.167	10.183	0.0159
557	1e+13	NDD	10.207	10.22	0.0127
558	1e+13	NDD	10.273	10.275	0.0025
559	0	NDD, Ctrl	10.393	10.439	0.0453

Test Statistics (mA)

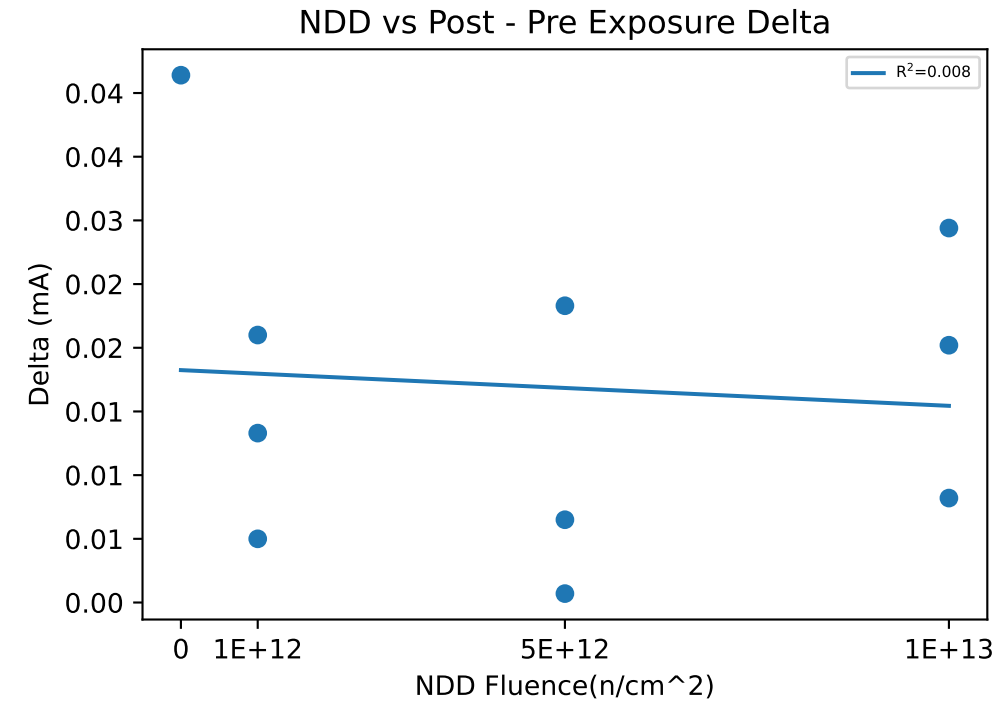
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	10.393	10.393	10.393		10.439	10.439	10.439		0.0453	0.0453	0.0453	
1e+12	10.109	10.265	10.406	0.14893	10.127	10.284	10.427	0.15027	0.0182	0.019167	0.021	0.0015885
5e+12	10.223	10.295	10.357	0.067482	10.231	10.305	10.361	0.066634	0.0046	0.010133	0.0173	0.0065056
1e+13	10.167	10.216	10.273	0.05336	10.183	10.226	10.275	0.046458	0.0025	0.010367	0.0159	0.0069981

Device Test: 37.19 I_OP_HS_IIM_2MHZ_INTERLOCK(Iop HS BOOT IIM Interlock 2MHz VIN_14V)



Test Results (Upper Limit = 10.5 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	6.9842	6.9975	0.0133
551	1e+12	NDD	6.8468	6.8678	0.021
552	1e+12	NDD	7.0152	7.0202	0.005
553	5e+12	NDD	7.0379	7.0612	0.0233
554	5e+12	NDD	7.0746	7.0811	0.0065
555	5e+12	NDD	6.9984	6.9991	0.0007
556	1e+13	NDD	6.8457	6.8539	0.0082
557	1e+13	NDD	6.8867	6.9069	0.0202
558	1e+13	NDD	7.1025	7.1319	0.0294
559	0	NDD, Ctrl	7.1124	7.1538	0.0414

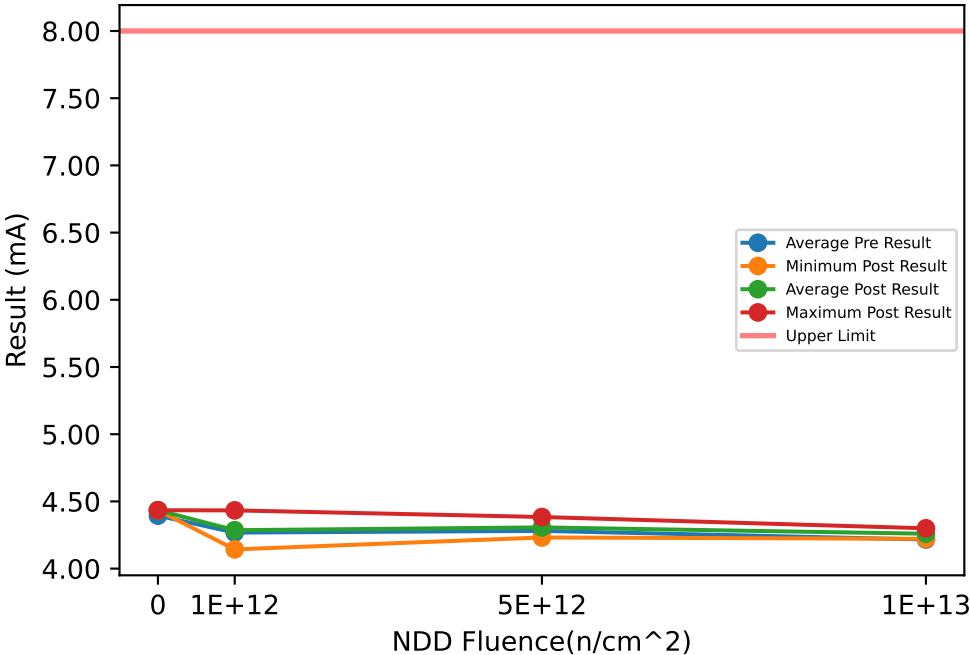


Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.1124	7.1124	7.1124		7.1538	7.1538	7.1538		0.0414	0.0414	0.0414	
1e+12	6.8468	6.9487	7.0152	0.089627	6.8678	6.9618	7.0202	0.082222	0.005	0.0131	0.021	0.0080019
5e+12	6.9984	7.037	7.0746	0.038109	6.9991	7.0471	7.0811	0.042772	0.0007	0.010167	0.0233	0.011738
1e+13	6.8457	6.945	7.1025	0.13796	6.8539	6.9642	7.1319	0.1476	0.0082	0.019267	0.0294	0.010631

Device Test: 37.2 IQ_LS_IIM_INTERLOCK(Iq LS VIN IIM Interlock VIN_14V)

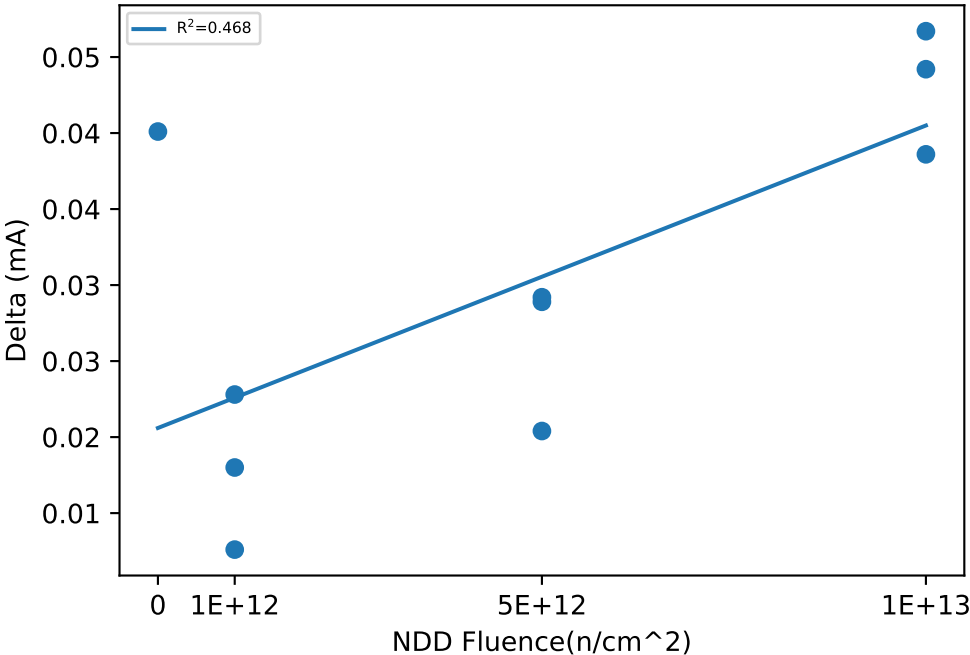
NDD vs Result Stats



Test Results (Upper Limit = 8.0 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.263	4.281	0.018
551	1e+12	NDD	4.1303	4.1429	0.0126
552	1e+12	NDD	4.4104	4.4332	0.0228
553	5e+12	NDD	4.2753	4.3045	0.0292
554	5e+12	NDD	4.3636	4.384	0.0204
555	5e+12	NDD	4.2026	4.2315	0.0289
556	1e+13	NDD	4.2104	4.2571	0.0467
557	1e+13	NDD	4.1775	4.2217	0.0442
558	1e+13	NDD	4.2611	4.2997	0.0386
559	0	NDD, Ctrl	4.3942	4.4343	0.0401

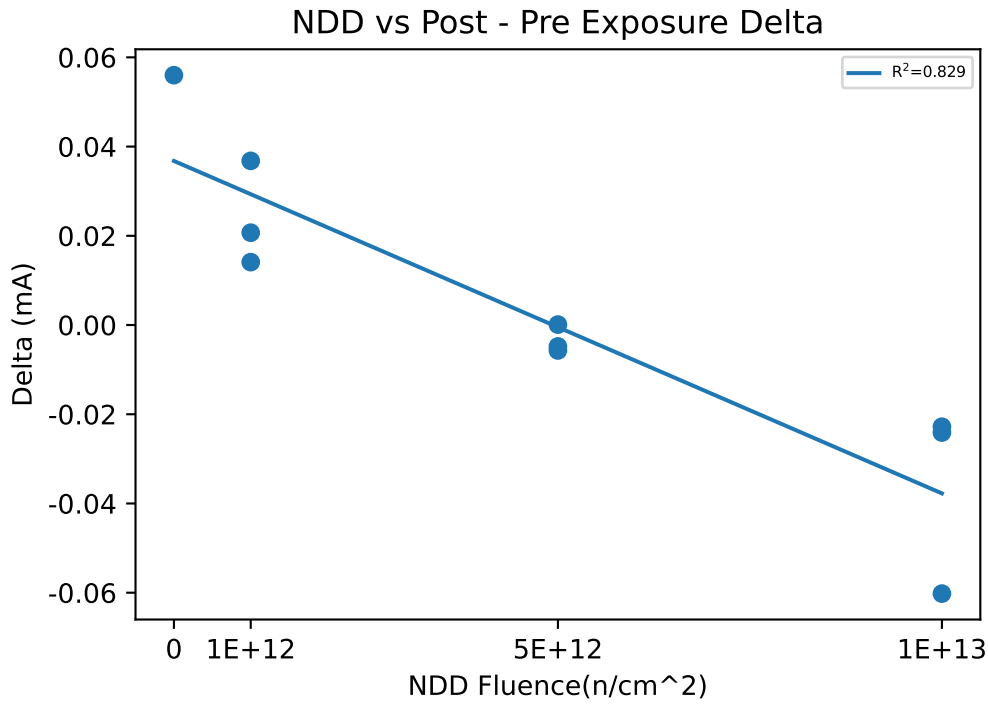
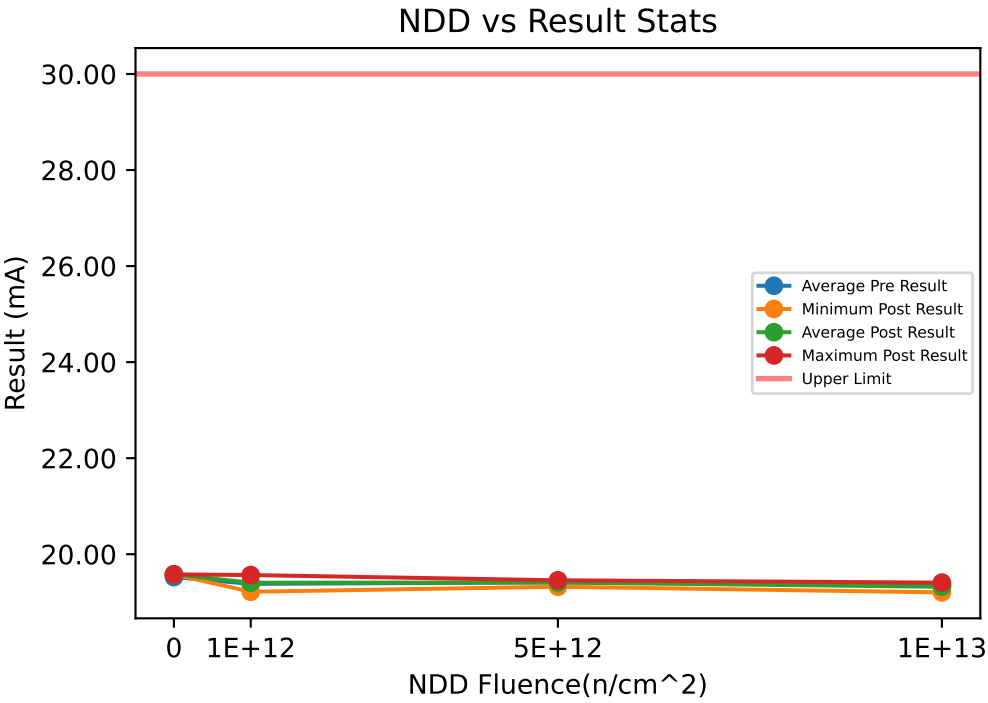
NDD vs Post - Pre Exposure Delta



Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.3942	4.3942	4.3942		4.4343	4.4343	4.4343		0.0401	0.0401	0.0401	
1e+12	4.1303	4.2679	4.4104	0.14011	4.1429	4.2857	4.4332	0.14521	0.0126	0.0178	0.0228	0.0051029
5e+12	4.2026	4.2805	4.3636	0.080626	4.2315	4.3067	4.384	0.076273	0.0204	0.026167	0.0292	0.0049963
1e+13	4.1775	4.2163	4.2611	0.042115	4.2217	4.2595	4.2997	0.039055	0.0386	0.043167	0.0467	0.0041477

Device Test: 37.20 I_OP_LS_IIM_5MHZ_INTERLOCK(Iop LS VIN IIM Interlock 5MHz VIN_14V)

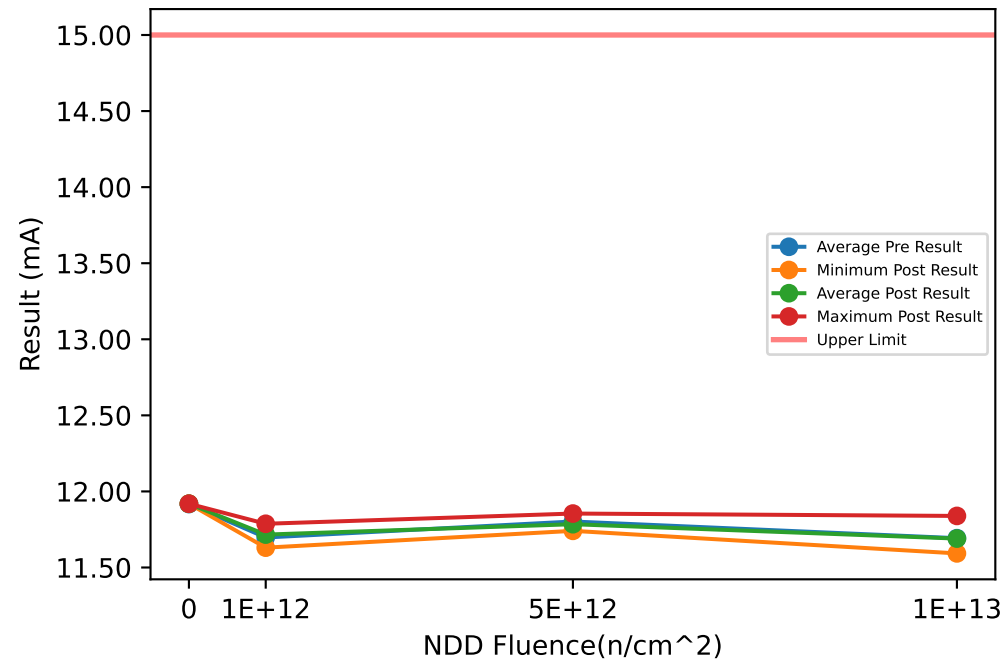


Test Results (Upper Limit = 30.0 (mA))					
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	19.414	19.435	0.0207
551	1e+12	NDD	19.204	19.218	0.0141
552	1e+12	NDD	19.529	19.566	0.0368
553	5e+12	NDD	19.462	19.457	-0.0057
554	5e+12	NDD	19.458	19.453	-0.0048
555	5e+12	NDD	19.323	19.323	0.0001
556	1e+13	NDD	19.227	19.205	-0.0228
557	1e+13	NDD	19.376	19.352	-0.0241
558	1e+13	NDD	19.468	19.408	-0.0602
559	0	NDD, Ctrl	19.524	19.58	0.056

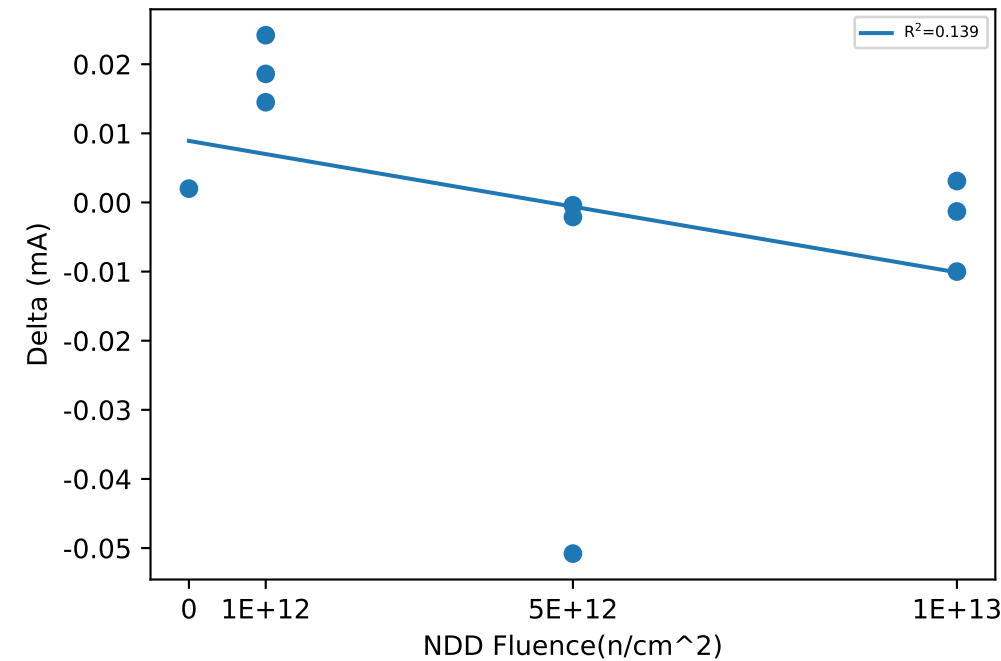
Test Statistics (mA)												
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	19.524	19.524	19.524		19.58	19.58	19.58		0.056	0.056	0.056	
1e+12	19.204	19.382	19.529	0.16473	19.218	19.406	19.566	0.17553	0.0141	0.023867	0.0368	0.011677
5e+12	19.323	19.414	19.462	0.079279	19.323	19.411	19.457	0.076179	-0.0057	-0.0034667	0.0001	0.0031214
1e+13	19.227	19.357	19.468	0.12156	19.205	19.322	19.408	0.10509	-0.0602	-0.0357	-0.0228	0.021228

Device Test: 37.21 I_OP_HS_IIM_5MHZ_INTERLOCK(Iop HS BOOT IIM Interlock 5MHz VIN_14V)

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 15.0 (mA))

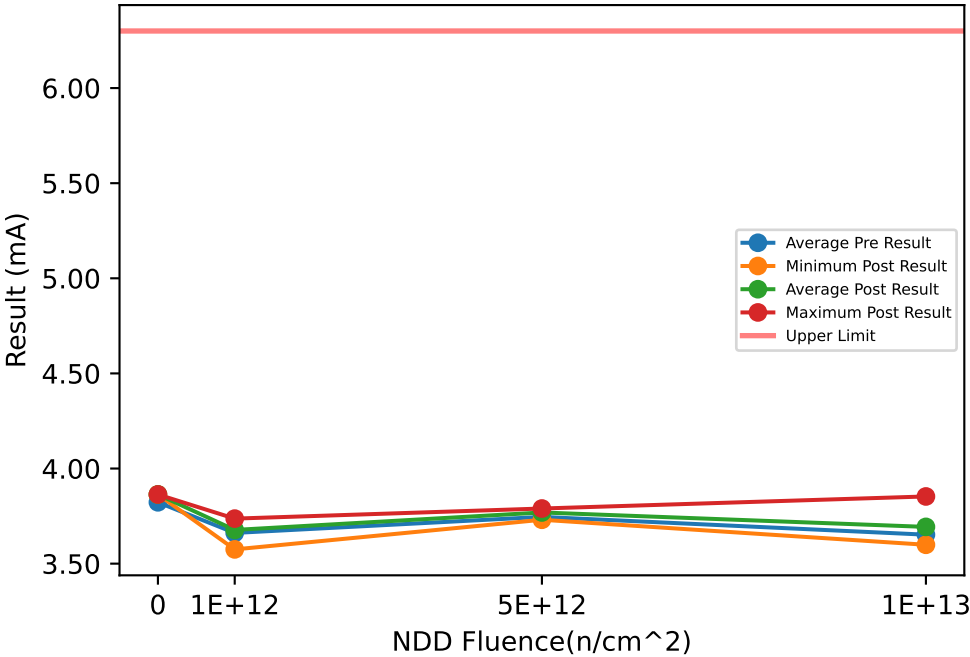
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	11.713	11.731	0.0186
551	1e+12	NDD	11.606	11.63	0.0242
552	1e+12	NDD	11.773	11.787	0.0145
553	5e+12	NDD	11.76	11.758	-0.0021
554	5e+12	NDD	11.855	11.855	-0.0004
555	5e+12	NDD	11.792	11.741	-0.0508
556	1e+13	NDD	11.603	11.593	-0.01
557	1e+13	NDD	11.635	11.639	0.0031
558	1e+13	NDD	11.84	11.839	-0.0013
559	0	NDD, Ctrl	11.917	11.919	0.002

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	11.917	11.917	11.917		11.919	11.919	11.919		0.002	0.002	0.002	
1e+12	11.606	11.697	11.773	0.084397	11.63	11.716	11.787	0.079539	0.0145	0.0191	0.0242	0.0048693
5e+12	11.76	11.802	11.855	0.048237	11.741	11.785	11.855	0.061264	-0.0508	-0.017767	-0.0004	0.02862
1e+13	11.603	11.693	11.84	0.12878	11.593	11.69	11.839	0.131	-0.01	-0.0027333	0.0031	0.0066666

Device Test: 37.3 IQ_HS_IIM_INTERLOCK(Iq HS BOOT IIM Interlock VIN_14V)

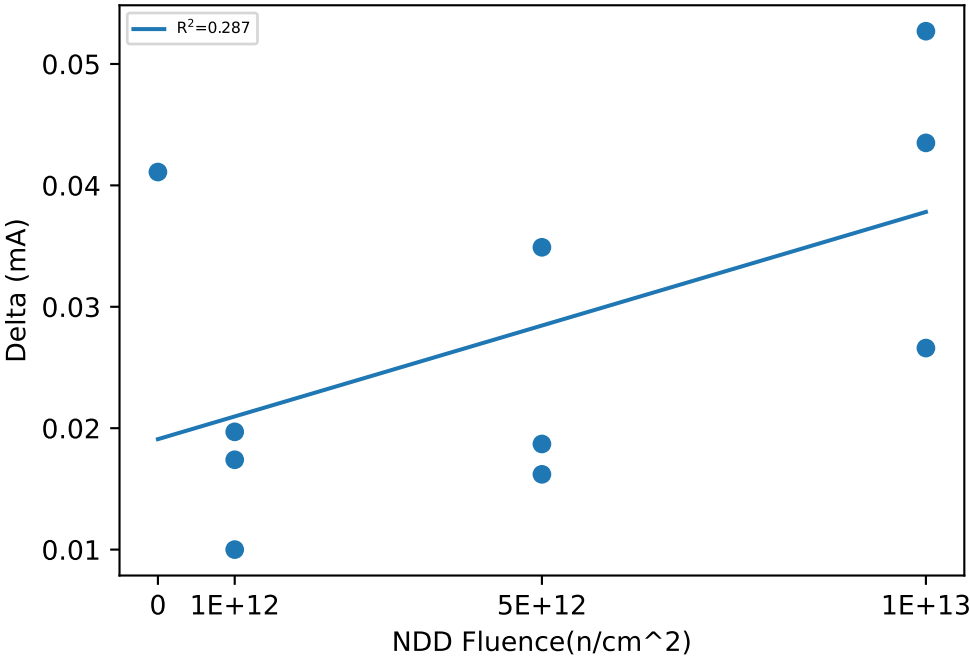
NDD vs Result Stats



Test Results (Upper Limit = 6.3 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	3.7026	3.72	0.0174
551	1e+12	NDD	3.5552	3.5749	0.0197
552	1e+12	NDD	3.7267	3.7367	0.01
553	5e+12	NDD	3.7517	3.7866	0.0349
554	5e+12	NDD	3.7711	3.7898	0.0187
555	5e+12	NDD	3.7145	3.7307	0.0162
556	1e+13	NDD	3.5726	3.5992	0.0266
557	1e+13	NDD	3.5837	3.6272	0.0435
558	1e+13	NDD	3.8005	3.8532	0.0527
559	0	NDD, Ctrl	3.8225	3.8636	0.0411

NDD vs Post - Pre Exposure Delta

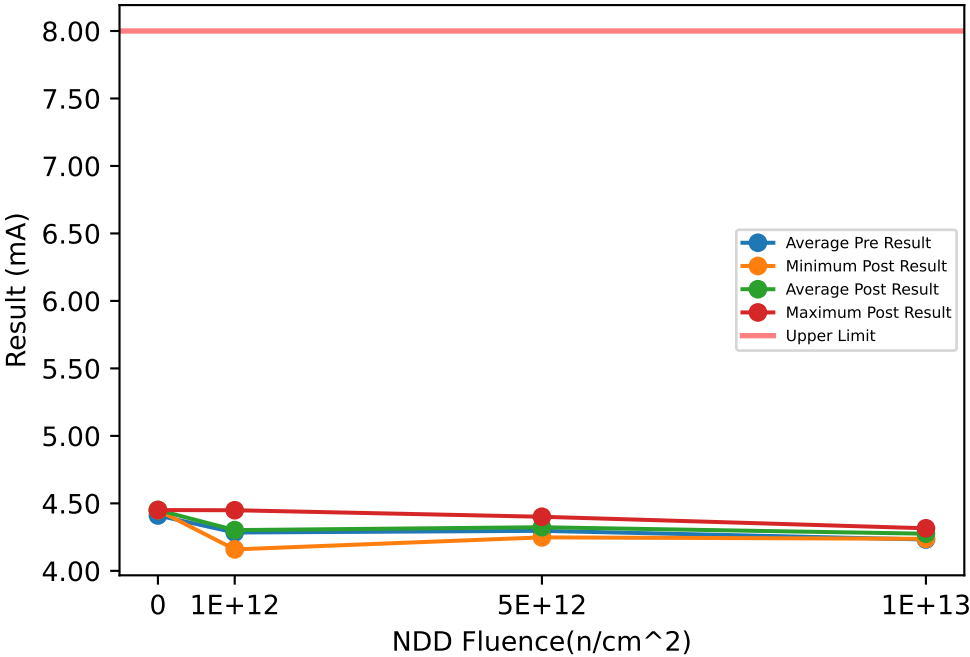


Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.8225	3.8225	3.8225		3.8636	3.8636	3.8636		0.0411	0.0411	0.0411	
1e+12	3.5552	3.6615	3.7267	0.092844	3.5749	3.6772	3.7367	0.088987	0.01	0.0157	0.0197	0.0050685
5e+12	3.7145	3.7458	3.7711	0.028763	3.7307	3.769	3.7898	0.033236	0.0162	0.023267	0.0349	0.010152
1e+13	3.5726	3.6523	3.8005	0.12849	3.5992	3.6932	3.8532	0.13927	0.0266	0.040933	0.0527	0.013238

Device Test: 37.4 IQ_LS_IIM_INTERLOCK_DIS(Iq LS VIN IIM Interlock Disable VIN_14V)

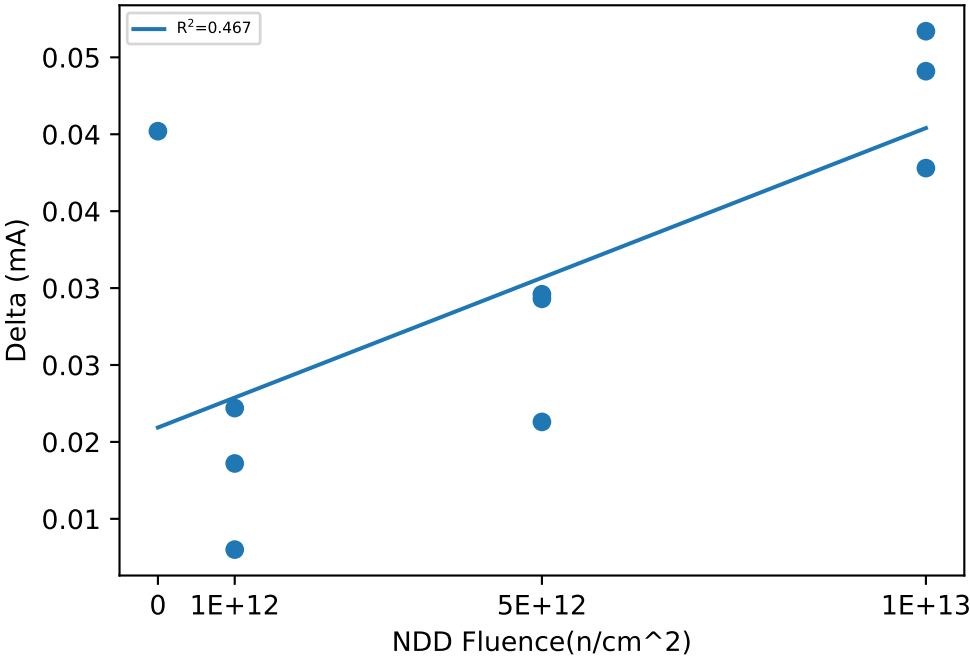
NDD vs Result Stats



Test Results (Upper Limit = 8.0 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.279	4.2976	0.0186
551	1e+12	NDD	4.146	4.159	0.013
552	1e+12	NDD	4.427	4.4492	0.0222
553	5e+12	NDD	4.2917	4.321	0.0293
554	5e+12	NDD	4.3795	4.4008	0.0213
555	5e+12	NDD	4.2184	4.248	0.0296
556	1e+13	NDD	4.2258	4.2725	0.0467
557	1e+13	NDD	4.1934	4.2375	0.0441
558	1e+13	NDD	4.2776	4.3154	0.0378
559	0	NDD, Ctrl	4.4102	4.4504	0.0402

NDD vs Post - Pre Exposure Delta

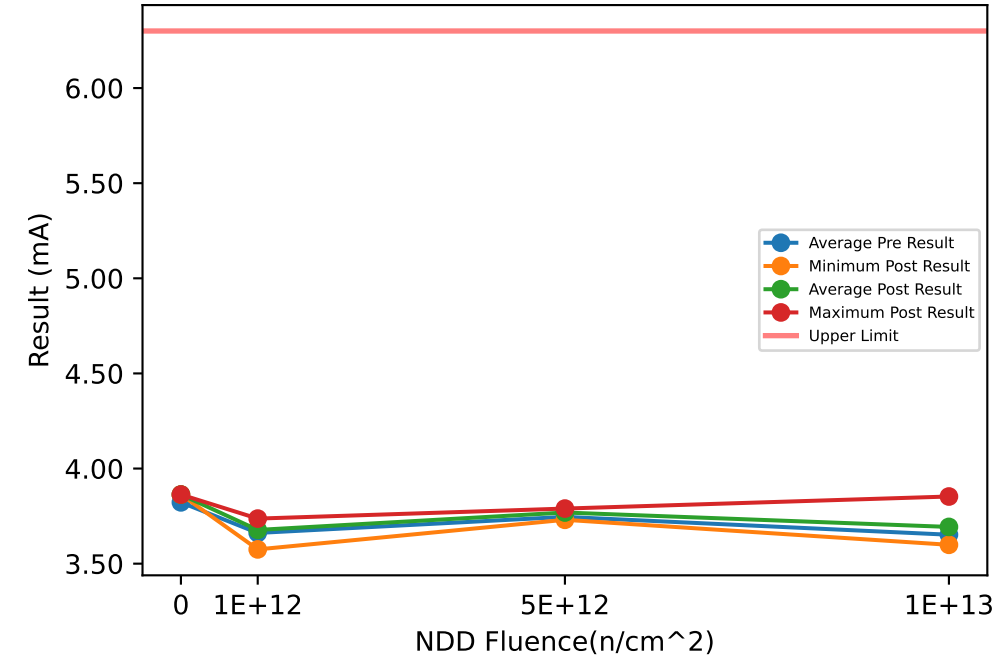


Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.4102	4.4102	4.4102		4.4504	4.4504	4.4504		0.0402	0.0402	0.0402	
1e+12	4.146	4.284	4.427	0.14057	4.159	4.3019	4.4492	0.14515	0.013	0.017933	0.0222	0.0046361
5e+12	4.2184	4.2965	4.3795	0.080659	4.248	4.3233	4.4008	0.076425	0.0213	0.026733	0.0296	0.0047078
1e+13	4.1934	4.2323	4.2776	0.042471	4.2375	4.2751	4.3154	0.039017	0.0378	0.042867	0.0467	0.0045764

Device Test: 37.5 IQ_HS_IIM_INTERLOCK_DIS(Iq HS BOOT IIM Interlock Disable VIN_14V)

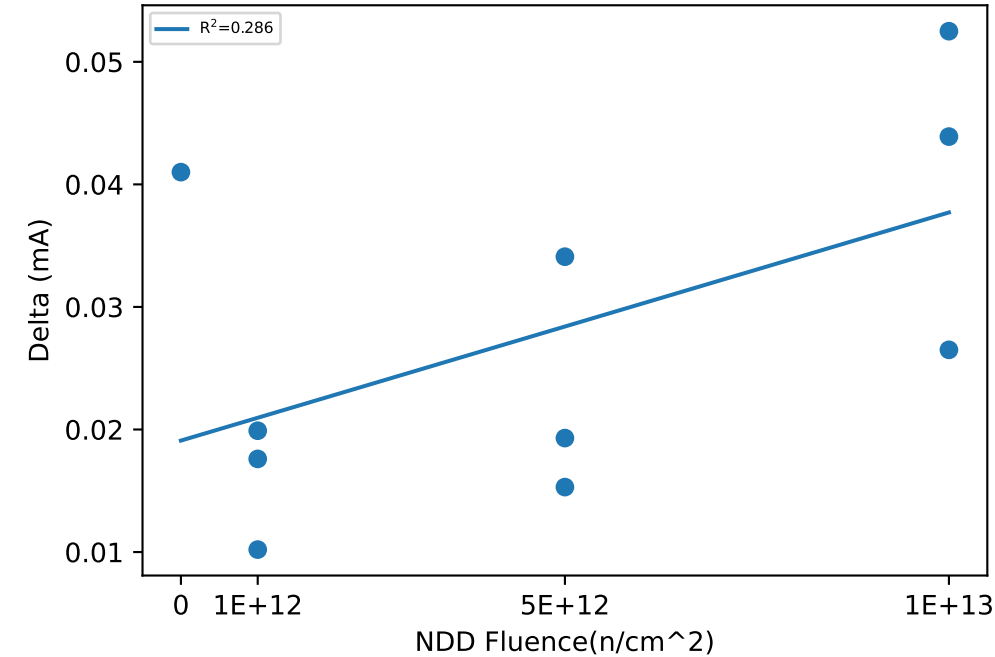
NDD vs Result Stats



Test Results (Upper Limit = 6.3 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	3.7025	3.7201	0.0176
551	1e+12	NDD	3.5551	3.575	0.0199
552	1e+12	NDD	3.7267	3.7369	0.0102
553	5e+12	NDD	3.7522	3.7863	0.0341
554	5e+12	NDD	3.7703	3.7896	0.0193
555	5e+12	NDD	3.7153	3.7306	0.0153
556	1e+13	NDD	3.5727	3.5992	0.0265
557	1e+13	NDD	3.5833	3.6272	0.0439
558	1e+13	NDD	3.8005	3.853	0.0525
559	0	NDD, Ctrl	3.8223	3.8633	0.041

NDD vs Post - Pre Exposure Delta

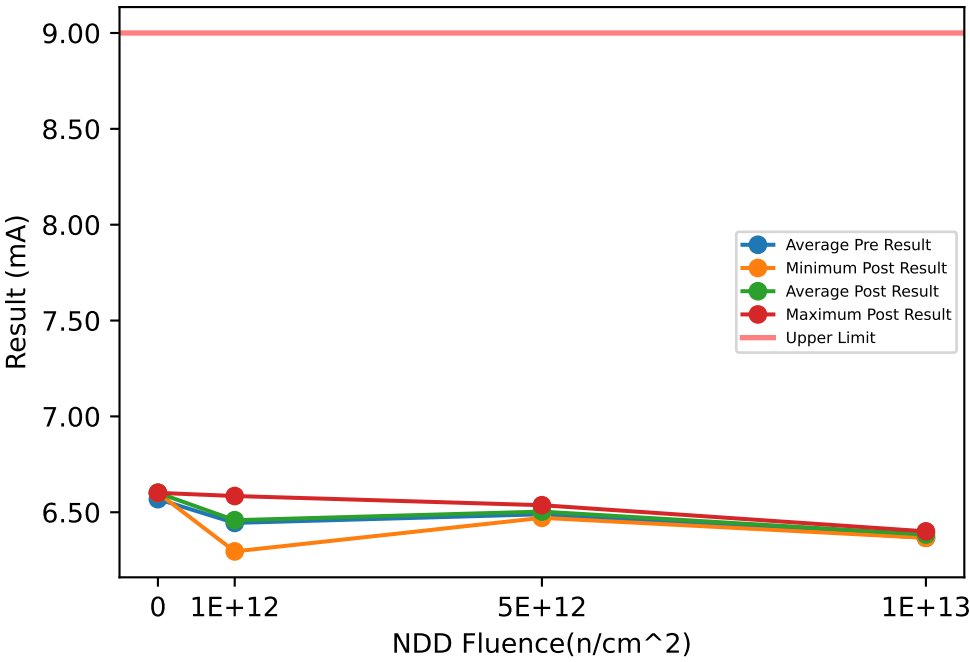


Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.8223	3.8223	3.8223		3.8633	3.8633	3.8633		0.041	0.041	0.041	
1e+12	3.5551	3.6614	3.7267	0.092879	3.575	3.6773	3.7369	0.08902	0.0102	0.0159	0.0199	0.0050685
5e+12	3.7153	3.7459	3.7703	0.02803	3.7306	3.7688	3.7896	0.033152	0.0153	0.0229	0.0341	0.0099035
1e+13	3.5727	3.6522	3.8005	0.12857	3.5992	3.6931	3.853	0.13915	0.0265	0.040967	0.0525	0.013246

Device Test: 37.6 I_OP_LS_PWM_500KHZ(Iop LS VIN PWM 500kHz VIN_14V)

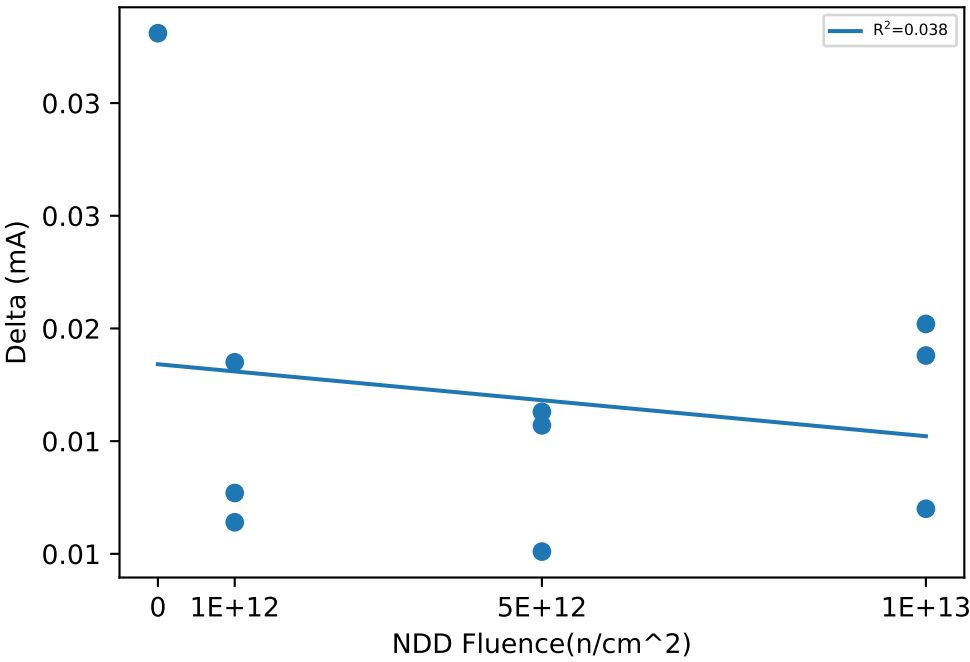
NDD vs Result Stats



Test Results (Upper Limit = 9.0 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	6.4824	6.4951	0.0127
551	1e+12	NDD	6.2844	6.2958	0.0114
552	1e+12	NDD	6.5662	6.5847	0.0185
553	5e+12	NDD	6.4865	6.5028	0.0163
554	5e+12	NDD	6.5267	6.5368	0.0101
555	5e+12	NDD	6.4552	6.4709	0.0157
556	1e+13	NDD	6.3648	6.385	0.0202
557	1e+13	NDD	6.3815	6.4003	0.0188
558	1e+13	NDD	6.3545	6.3665	0.012
559	0	NDD, Ctrl	6.5682	6.6013	0.0331

NDD vs Post - Pre Exposure Delta

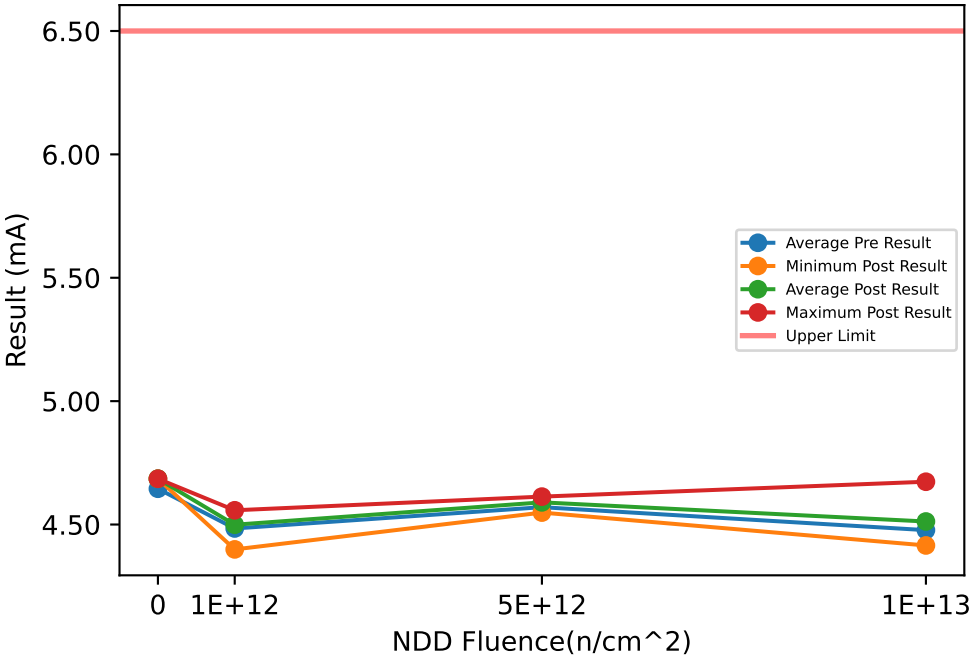


Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.5682	6.5682	6.5682		6.6013	6.6013	6.6013		0.0331	0.0331	0.0331	
1e+12	6.2844	6.4443	6.5662	0.14471	6.2958	6.4585	6.5847	0.14788	0.0114	0.0142	0.0185	0.0037802
5e+12	6.4552	6.4895	6.5267	0.035842	6.4709	6.5035	6.5368	0.032956	0.0101	0.014033	0.0163	0.0034196
1e+13	6.3545	6.3669	6.3815	0.013626	6.3665	6.3839	6.4003	0.016925	0.012	0.017	0.0202	0.0043863

Device Test: 37.7 I_OP_HS_PWM_500KHZ(lop HS BOOT PWM 500kHz VIN_14V)

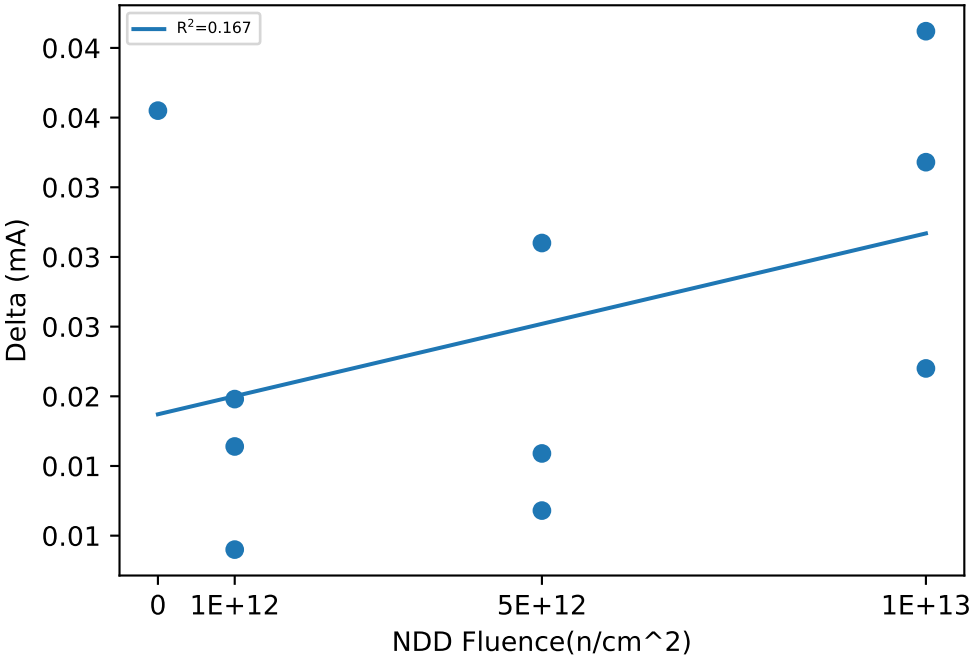
NDD vs Result Stats



Test Results (Upper Limit = 6.5 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.5241	4.5405	0.0164
551	1e+12	NDD	4.3794	4.3992	0.0198
552	1e+12	NDD	4.5487	4.5577	0.009
553	5e+12	NDD	4.577	4.608	0.031
554	5e+12	NDD	4.5972	4.6131	0.0159
555	5e+12	NDD	4.5366	4.5484	0.0118
556	1e+13	NDD	4.3932	4.4152	0.022
557	1e+13	NDD	4.4114	4.4482	0.0368
558	1e+13	NDD	4.6272	4.6734	0.0462
559	0	NDD, Ctrl	4.645	4.6855	0.0405

NDD vs Post - Pre Exposure Delta

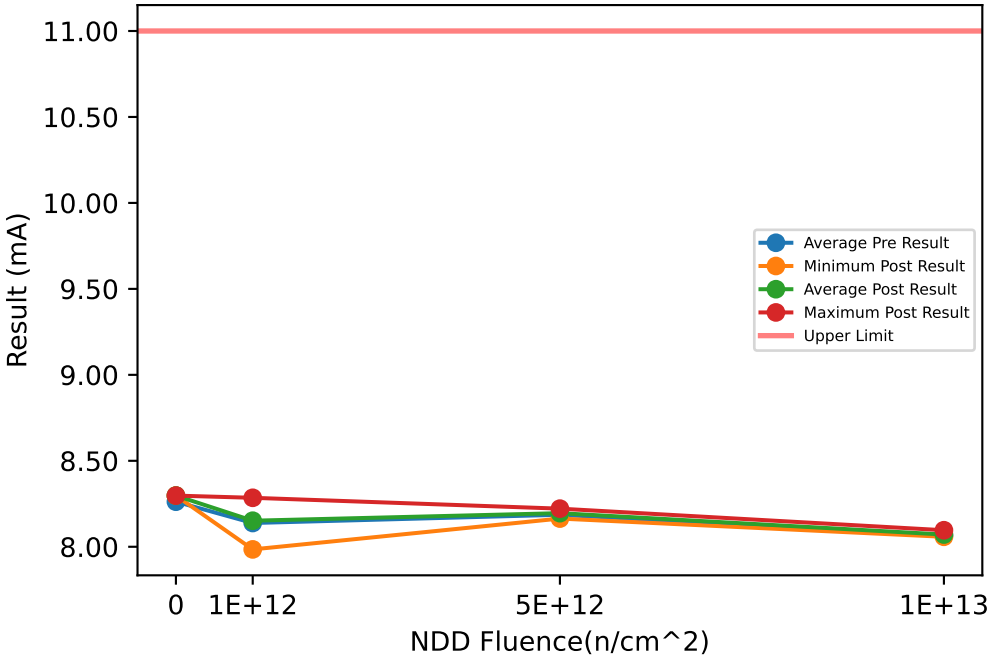


Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.645	4.645	4.645		4.6855	4.6855	4.6855		0.0405	0.0405	0.0405	
1e+12	4.3794	4.4841	4.5487	0.091475	4.3992	4.4991	4.5577	0.086971	0.009	0.015067	0.0198	0.0055221
5e+12	4.5366	4.5703	4.5972	0.030856	4.5484	4.5898	4.6131	0.035973	0.0118	0.019567	0.031	0.010112
1e+13	4.3932	4.4773	4.6272	0.13016	4.4152	4.5123	4.6734	0.14052	0.022	0.035	0.0462	0.0122

Device Test: 37.8 I_OP_LS_PWM_1MHZ(Iop LS VIN PWM 1MHz VIN_14V)

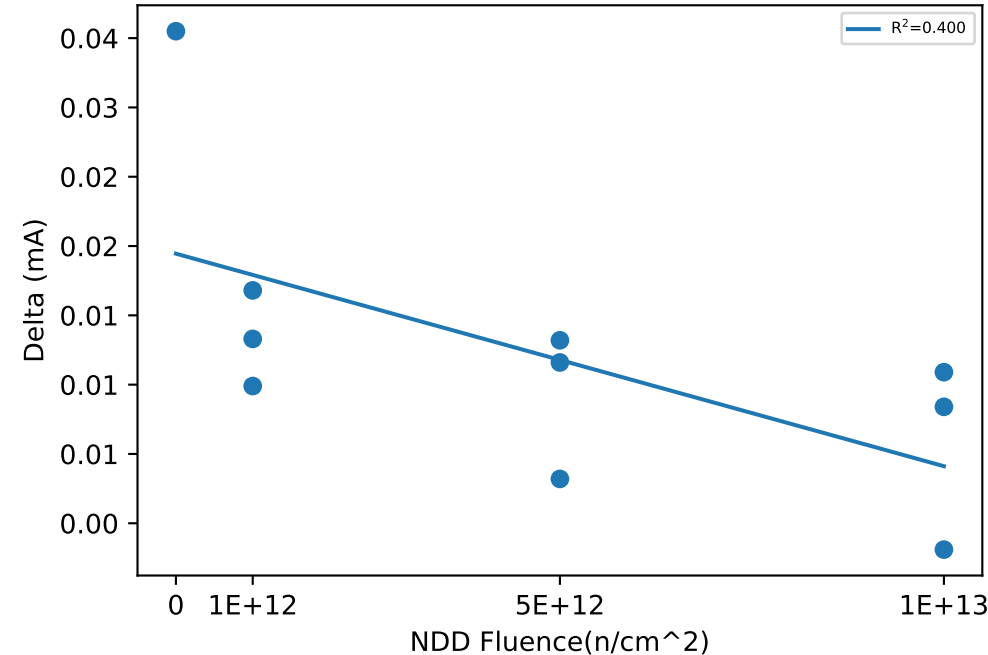
NDD vs Result Stats



Test Results (Upper Limit = 11.0 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	8.1719	8.1852	0.0133
551	1e+12	NDD	7.9748	7.9847	0.0099
552	1e+12	NDD	8.268	8.2848	0.0168
553	5e+12	NDD	8.1875	8.2007	0.0132
554	5e+12	NDD	8.2185	8.2217	0.0032
555	5e+12	NDD	8.1524	8.164	0.0116
556	1e+13	NDD	8.0482	8.0591	0.0109
557	1e+13	NDD	8.0878	8.0962	0.0084
558	1e+13	NDD	8.0599	8.058	-0.0019
559	0	NDD, Ctrl	8.2621	8.2976	0.0355

NDD vs Post - Pre Exposure Delta

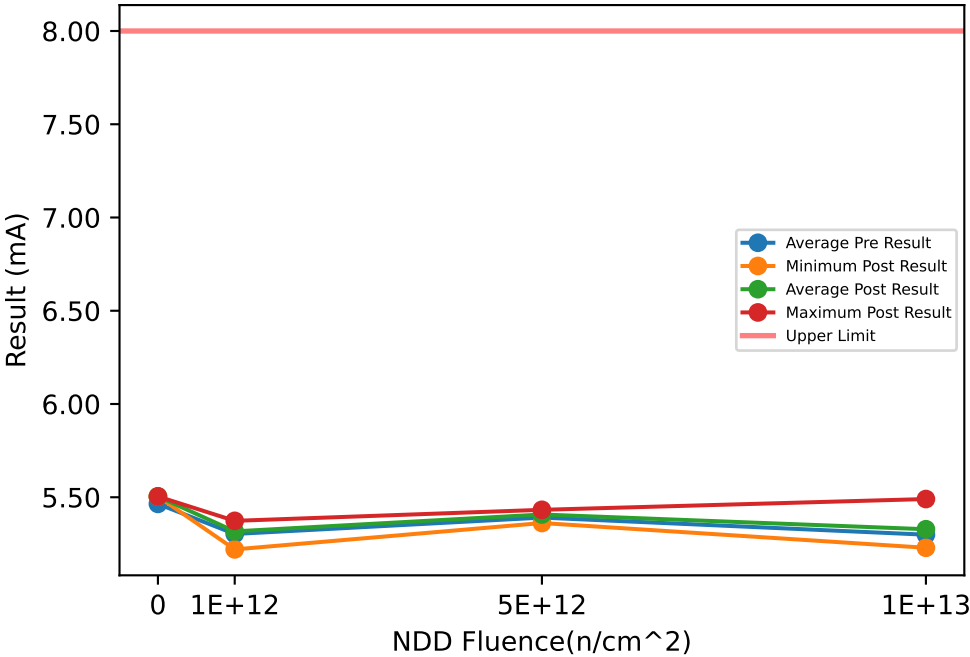


Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.2621	8.2621	8.2621		8.2976	8.2976	8.2976		0.0355	0.0355	0.0355	
1e+12	7.9748	8.1382	8.268	0.14947	7.9847	8.1516	8.2848	0.15285	0.0099	0.013333	0.0168	0.0034501
5e+12	8.1524	8.1861	8.2185	0.033071	8.164	8.1955	8.2217	0.029204	0.0032	0.0093333	0.0132	0.0053715
1e+13	8.0482	8.0653	8.0878	0.020345	8.058	8.0711	8.0962	0.021744	-0.0019	0.0058	0.0109	0.0067845

Device Test: 37.9 I_OP_HS_PWM_1MHZ(lop HS BOOT PWM 1MHz VIN_14V)

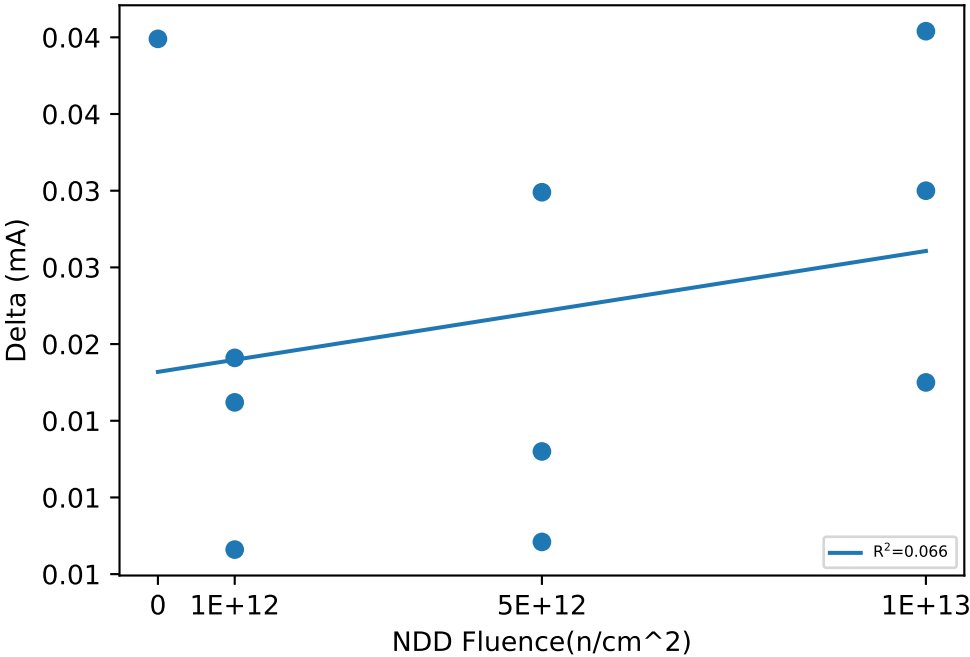
NDD vs Result Stats



Test Results (Upper Limit = 8.0 (mA))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	5.3411	5.3573	0.0162
551	1e+12	NDD	5.2013	5.2204	0.0191
552	1e+12	NDD	5.3669	5.3735	0.0066
553	5e+12	NDD	5.3983	5.4282	0.0299
554	5e+12	NDD	5.4196	5.4326	0.013
555	5e+12	NDD	5.3548	5.3619	0.0071
556	1e+13	NDD	5.2116	5.2291	0.0175
557	1e+13	NDD	5.2361	5.2661	0.03
558	1e+13	NDD	5.45	5.4904	0.0404
559	0	NDD, Ctrl	5.4644	5.5043	0.0399

NDD vs Post - Pre Exposure Delta

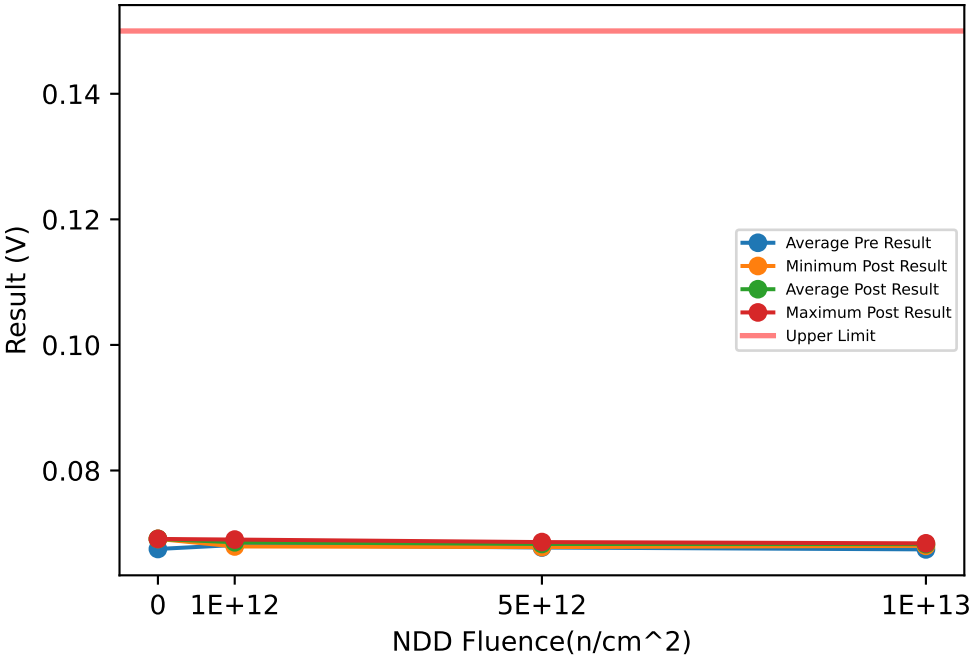


Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.4644	5.4644	5.4644		5.5043	5.5043	5.5043		0.0399	0.0399	0.0399	
1e+12	5.2013	5.3031	5.3669	0.0891	5.2204	5.3171	5.3735	0.084107	0.0066	0.013967	0.0191	0.0065424
5e+12	5.3548	5.3909	5.4196	0.033028	5.3619	5.4076	5.4326	0.03961	0.0071	0.016667	0.0299	0.011834
1e+13	5.2116	5.2992	5.45	0.13114	5.2291	5.3285	5.4904	0.1414	0.0175	0.0293	0.0404	0.011466

Device Test: 45.0 V_LS_OL(VOL LO VIN_10V)

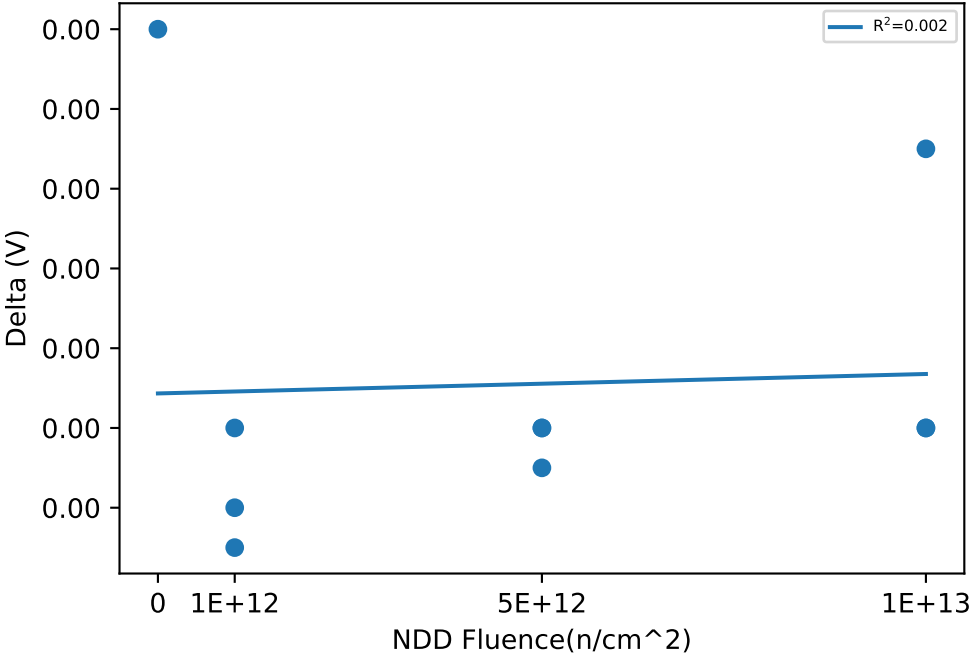
NDD vs Result Stats



Test Results (Upper Limit = 0.15 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	0.0686	0.069	0.0004
551	1e+12	NDD	0.0676	0.0679	0.0003
552	1e+12	NDD	0.0682	0.0688	0.0006
553	5e+12	NDD	0.0679	0.0685	0.0006
554	5e+12	NDD	0.0681	0.0686	0.0005
555	5e+12	NDD	0.0672	0.0678	0.0006
556	1e+13	NDD	0.0678	0.0684	0.0006
557	1e+13	NDD	0.0674	0.068	0.0006
558	1e+13	NDD	0.0671	0.0684	0.0013
559	0	NDD, Ctrl	0.0675	0.0691	0.0016

NDD vs Post - Pre Exposure Delta

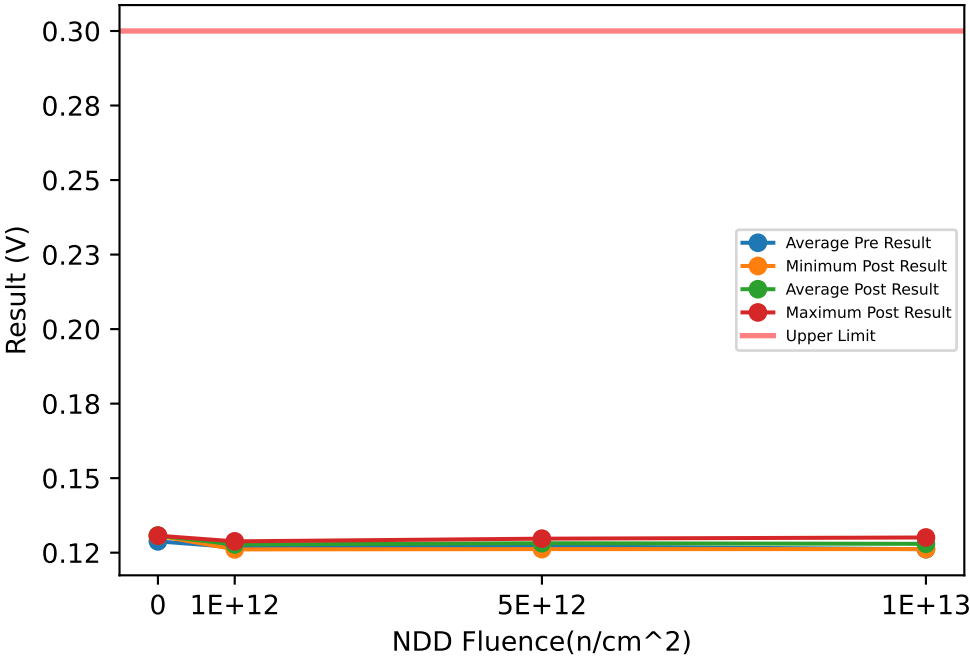


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0675	0.0675	0.0675		0.0691	0.0691	0.0691		0.0016	0.0016	0.0016	
1e+12	0.0676	0.068133	0.0686	0.00050332	0.0679	0.068567	0.069	0.00058595	0.0003	0.00043333	0.0006	0.00015275
5e+12	0.0672	0.067733	0.0681	0.00047258	0.0678	0.0683	0.0686	0.00043589	0.0005	0.00056667	0.0006	5.7735e-05
1e+13	0.0671	0.067433	0.0678	0.00035119	0.068	0.068267	0.0684	0.00023094	0.0006	0.00083333	0.0013	0.00040415

Device Test: 45.2 V_LS_OH_DELTA(VOH Delta LO VIN_10V)

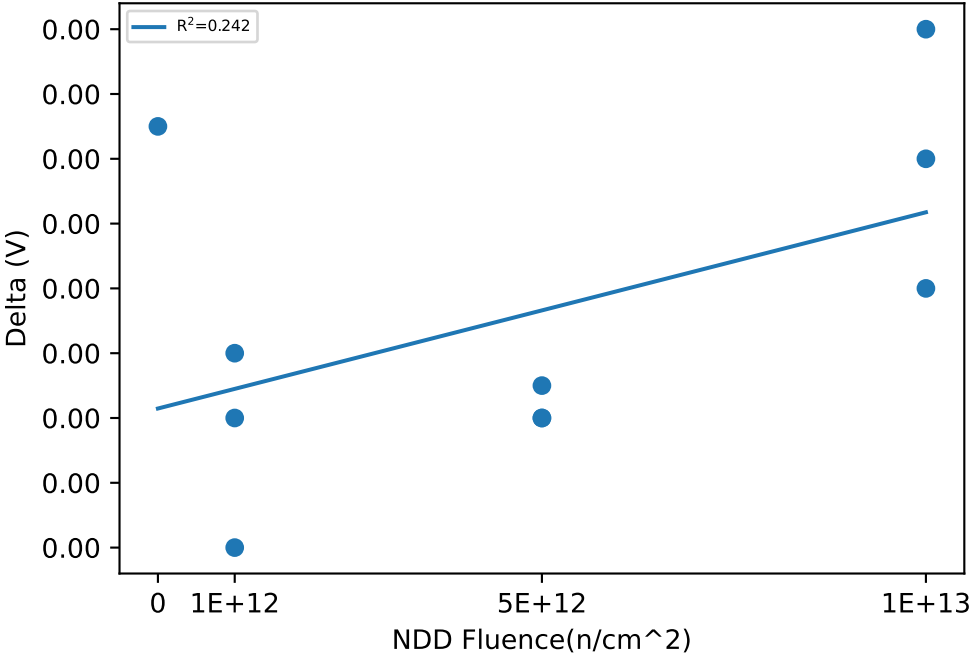
NDD vs Result Stats



Test Results (Upper Limit = 0.3 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	0.1278	0.1288	0.001
551	1e+12	NDD	0.1255	0.1261	0.0006
552	1e+12	NDD	0.1272	0.1284	0.0012
553	5e+12	NDD	0.1276	0.1286	0.001
554	5e+12	NDD	0.1286	0.1297	0.0011
555	5e+12	NDD	0.1252	0.1262	0.001
556	1e+13	NDD	0.1248	0.1262	0.0014
557	1e+13	NDD	0.1258	0.1276	0.0018
558	1e+13	NDD	0.1279	0.1301	0.0022
559	0	NDD, Ctrl	0.1288	0.1307	0.0019

NDD vs Post - Pre Exposure Delta

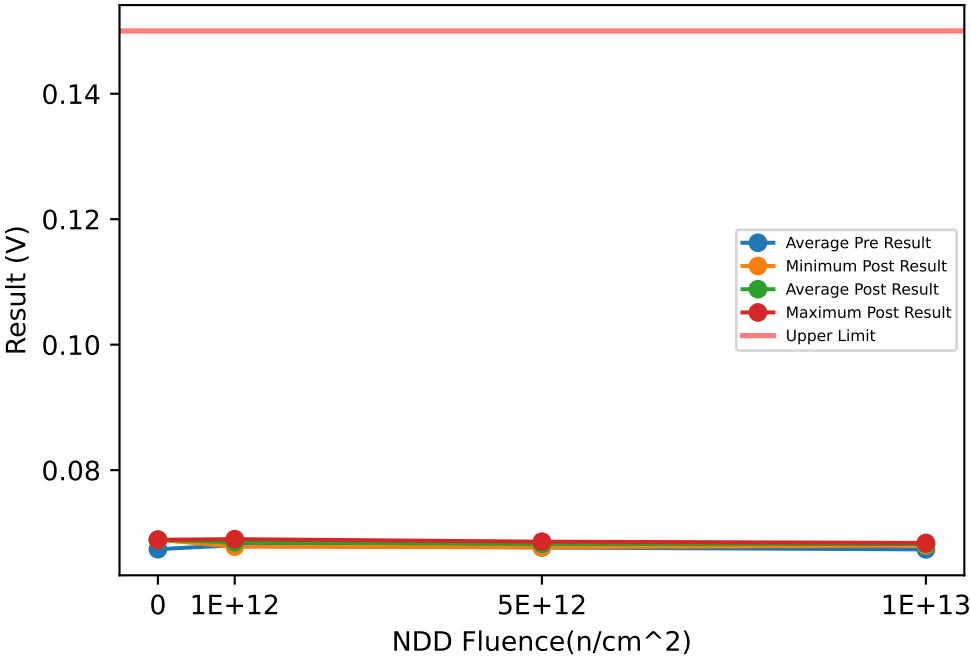


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1288	0.1288	0.1288		0.1307	0.1307	0.1307		0.0019	0.0019	0.0019	
1e+12	0.1255	0.12683	0.1278	0.001193	0.1261	0.12777	0.1288	0.0014572	0.0006	0.00093333	0.0012	0.00030551
5e+12	0.1252	0.12713	0.1286	0.0017474	0.1262	0.12817	0.1297	0.0017898	0.001	0.0010333	0.0011	5.7735e-05
1e+13	0.1248	0.12617	0.1279	0.0015822	0.1262	0.12797	0.1301	0.0019757	0.0014	0.0018	0.0022	0.0004

Device Test: 46.0 V_LS_OL(VOL LO VIN_12V)

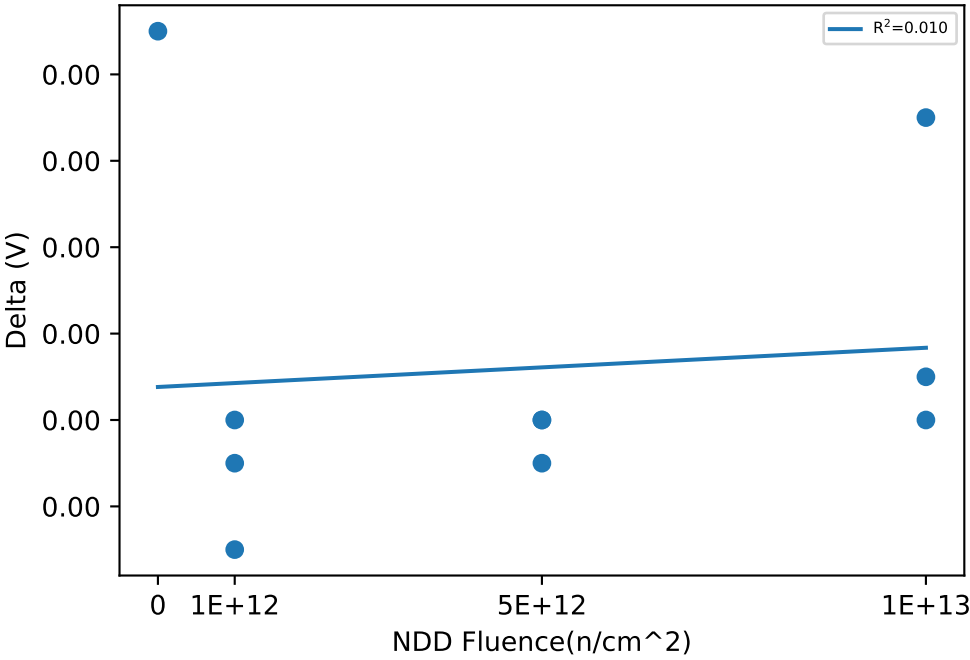
NDD vs Result Stats



Test Results (Upper Limit = 0.15 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	0.0685	0.069	0.0005
551	1e+12	NDD	0.0675	0.0678	0.0003
552	1e+12	NDD	0.0681	0.0687	0.0006
553	5e+12	NDD	0.0679	0.0684	0.0005
554	5e+12	NDD	0.068	0.0686	0.0006
555	5e+12	NDD	0.0671	0.0677	0.0006
556	1e+13	NDD	0.0678	0.0684	0.0006
557	1e+13	NDD	0.0673	0.068	0.0007
558	1e+13	NDD	0.067	0.0683	0.0013
559	0	NDD, Ctrl	0.0674	0.0689	0.0015

NDD vs Post - Pre Exposure Delta

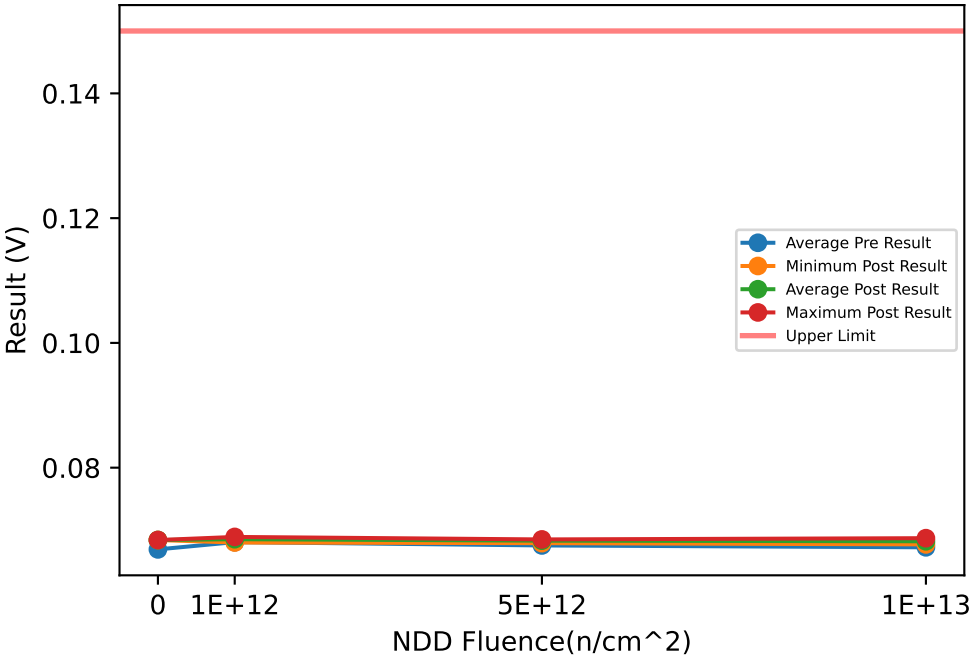


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0674	0.0674	0.0674		0.0689	0.0689	0.0689		0.0015	0.0015	0.0015	
1e+12	0.0675	0.068033	0.0685	0.00050332	0.0678	0.0685	0.069	0.0006245	0.0003	0.00046667	0.0006	0.00015275
5e+12	0.0671	0.067667	0.068	0.00049329	0.0677	0.068233	0.0686	0.00047258	0.0005	0.00056667	0.0006	5.7735e-05
1e+13	0.067	0.067367	0.0678	0.00040415	0.068	0.068233	0.0684	0.00020817	0.0006	0.00086667	0.0013	0.00037859

Device Test: 46.1 V_HS_OL(VOL HO VIN_12V)

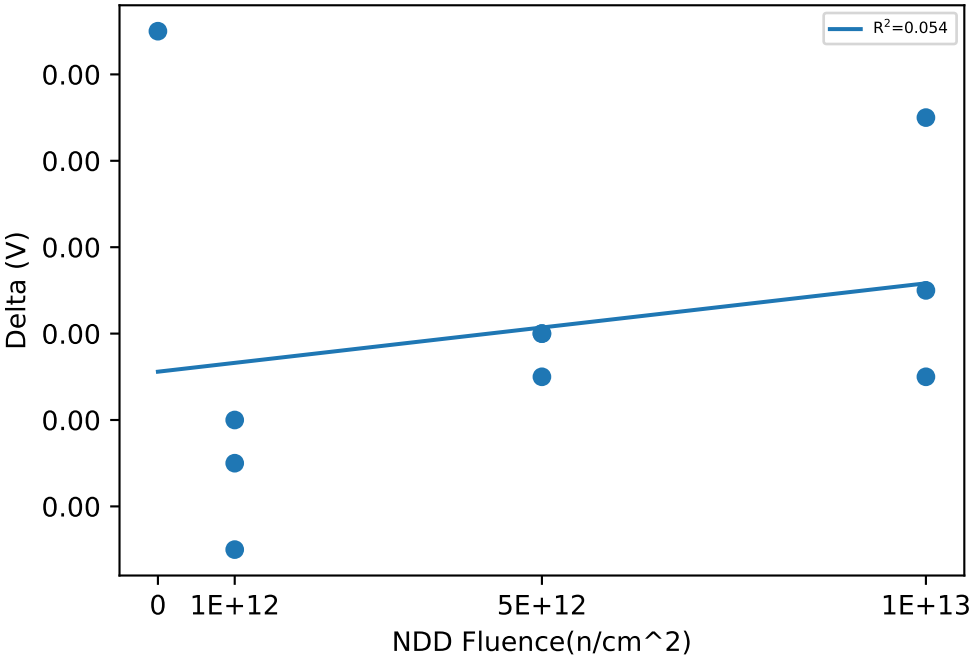
NDD vs Result Stats



Test Results (Upper Limit = 0.15 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	0.0684	0.0689	0.0005
551	1e+12	NDD	0.0677	0.068	0.0003
552	1e+12	NDD	0.0681	0.0687	0.0006
553	5e+12	NDD	0.0677	0.0685	0.0008
554	5e+12	NDD	0.0677	0.0685	0.0008
555	5e+12	NDD	0.0672	0.0679	0.0007
556	1e+13	NDD	0.0675	0.0682	0.0007
557	1e+13	NDD	0.0668	0.0677	0.0009
558	1e+13	NDD	0.0674	0.0687	0.0013
559	0	NDD, Ctrl	0.0669	0.0684	0.0015

NDD vs Post - Pre Exposure Delta

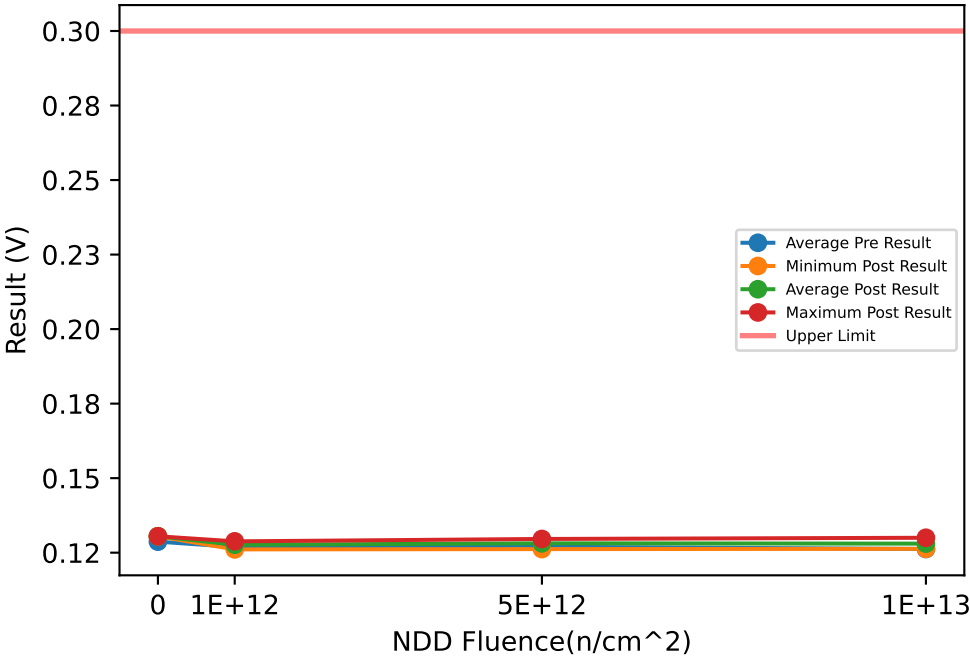


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0669	0.0669	0.0669		0.0684	0.0684	0.0684		0.0015	0.0015	0.0015	
1e+12	0.0677	0.068067	0.0684	0.00035119	0.068	0.068533	0.0689	0.00047258	0.0003	0.00046667	0.0006	0.00015275
5e+12	0.0672	0.067533	0.0677	0.00028868	0.0679	0.0683	0.0685	0.00034641	0.0007	0.00076667	0.0008	5.7735e-05
1e+13	0.0668	0.067233	0.0675	0.00037859	0.0677	0.0682	0.0687	0.0005	0.0007	0.00096667	0.0013	0.00030551

Device Test: 46.2 V_LS_OH_DELTA(VOH Delta LO VIN_12V)

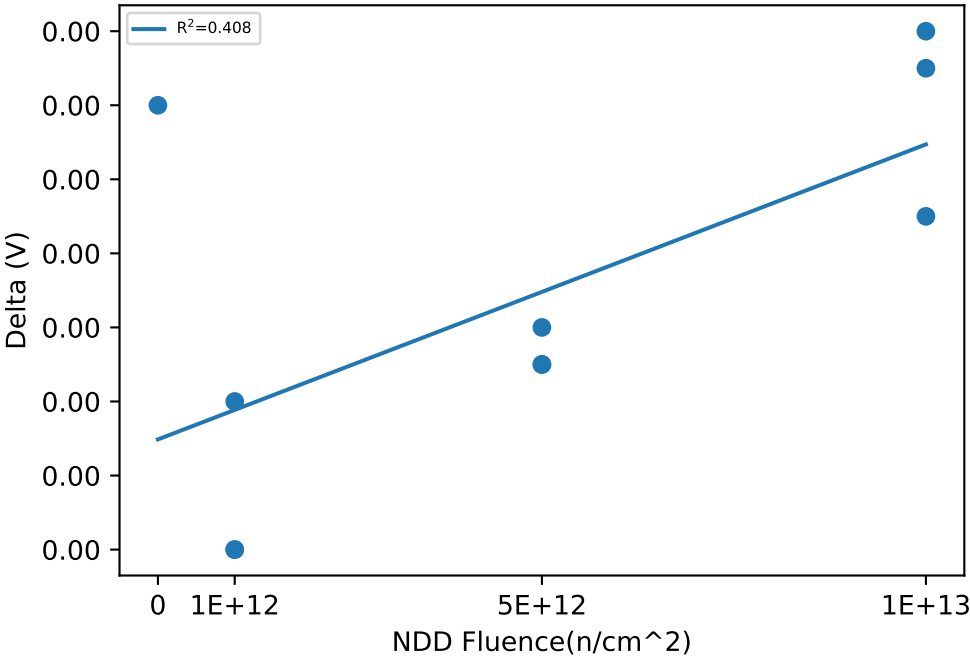
NDD vs Result Stats



Test Results (Upper Limit = 0.3 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	0.1278	0.1288	0.001
551	1e+12	NDD	0.1255	0.1261	0.0006
552	1e+12	NDD	0.1275	0.1281	0.0006
553	5e+12	NDD	0.1275	0.1286	0.0011
554	5e+12	NDD	0.1284	0.1296	0.0012
555	5e+12	NDD	0.1251	0.1262	0.0011
556	1e+13	NDD	0.1248	0.1263	0.0015
557	1e+13	NDD	0.1259	0.1278	0.0019
558	1e+13	NDD	0.128	0.13	0.002
559	0	NDD, Ctrl	0.1287	0.1305	0.0018

NDD vs Post - Pre Exposure Delta

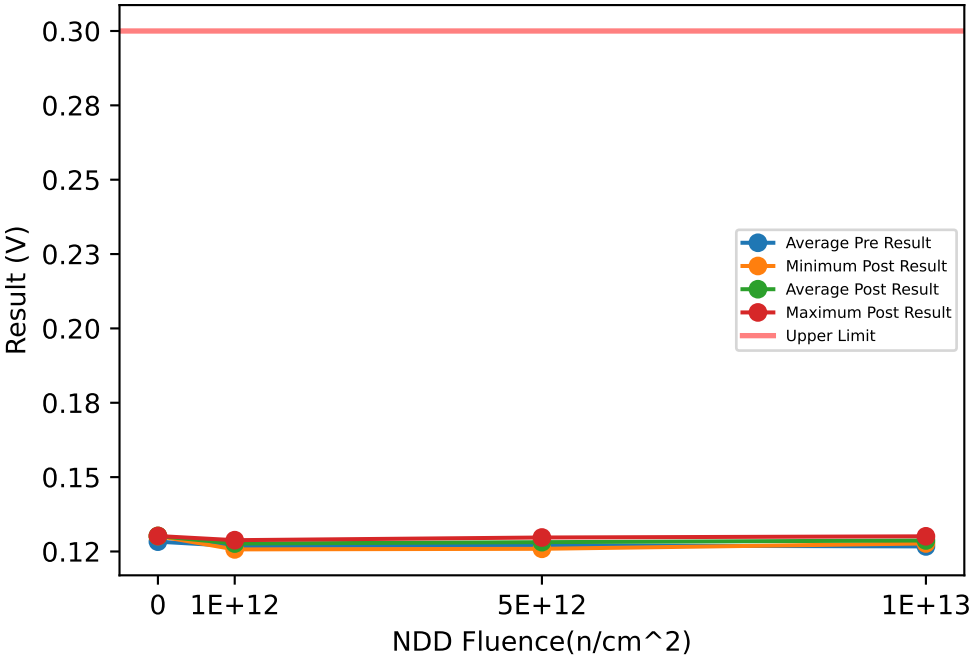


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1287	0.1287	0.1287		0.1305	0.1305	0.1305		0.0018	0.0018	0.0018	
1e+12	0.1255	0.12693	0.1278	0.0012503	0.1261	0.12767	0.1288	0.0014012	0.0006	0.00073333	0.001	0.00023094
5e+12	0.1251	0.127	0.1284	0.0017059	0.1262	0.12813	0.1296	0.0017474	0.0011	0.0011333	0.0012	5.7735e-05
1e+13	0.1248	0.12623	0.128	0.0016258	0.1263	0.12803	0.13	0.001861	0.0015	0.0018	0.002	0.00026458

Device Test: 46.3 V_HS_OH_DELTA(VOH Delta HO VIN_12V)

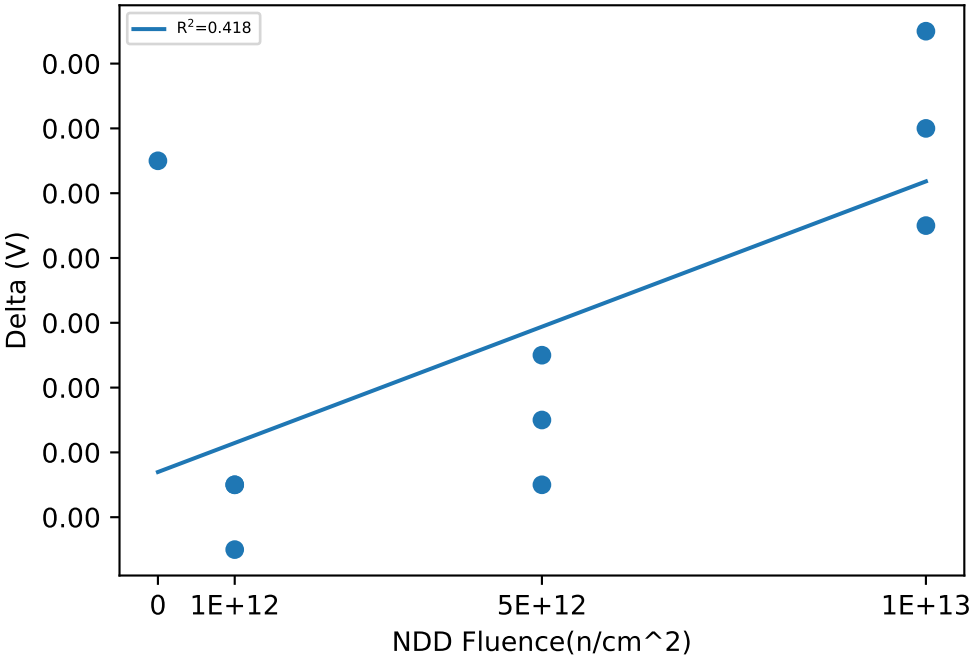
NDD vs Result Stats



Test Results (Upper Limit = 0.3 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	0.1276	0.1285	0.0009
551	1e+12	NDD	0.1248	0.1257	0.0009
552	1e+12	NDD	0.1281	0.1288	0.0007
553	5e+12	NDD	0.1284	0.1297	0.0013
554	5e+12	NDD	0.1277	0.1288	0.0011
555	5e+12	NDD	0.125	0.1259	0.0009
556	1e+13	NDD	0.126	0.1277	0.0017
557	1e+13	NDD	0.1263	0.1283	0.002
558	1e+13	NDD	0.1278	0.1301	0.0023
559	0	NDD, Ctrl	0.1283	0.1302	0.0019

NDD vs Post - Pre Exposure Delta

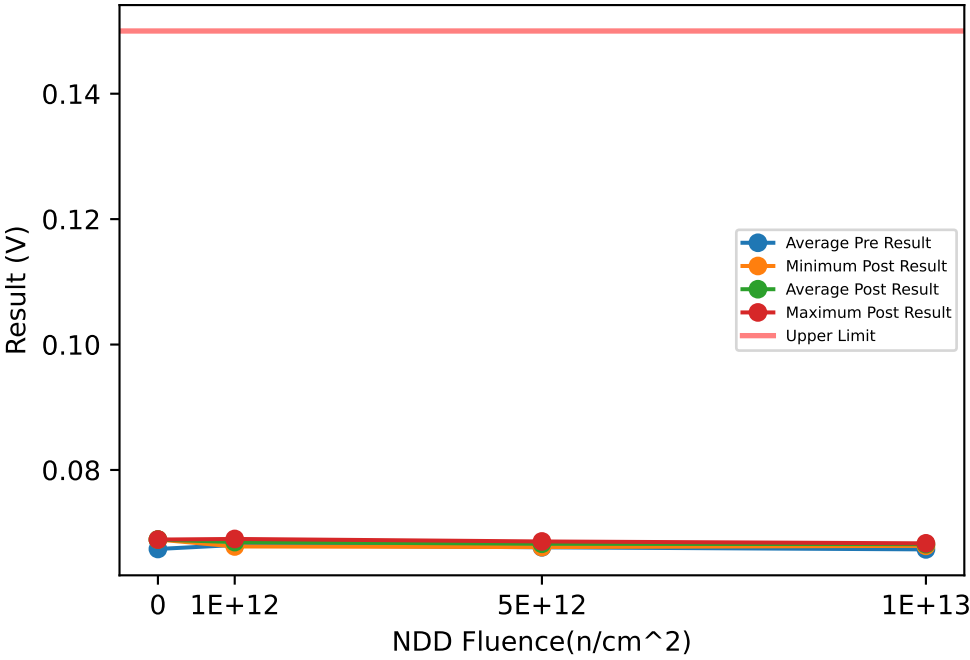


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1283	0.1283	0.1283		0.1302	0.1302	0.1302		0.0019	0.0019	0.0019	
1e+12	0.1248	0.12683	0.1281	0.0017786	0.1257	0.12767	0.1288	0.0017098	0.0007	0.00083333	0.0009	0.00011547
5e+12	0.125	0.12703	0.1284	0.0017954	0.1259	0.12813	0.1297	0.0019858	0.0009	0.0011	0.0013	0.0002
1e+13	0.126	0.1267	0.1278	0.00096437	0.1277	0.1287	0.1301	0.001249	0.0017	0.002	0.0023	0.0003

Device Test: 47.0 V_LS_OL(VOL LO VIN_14V)

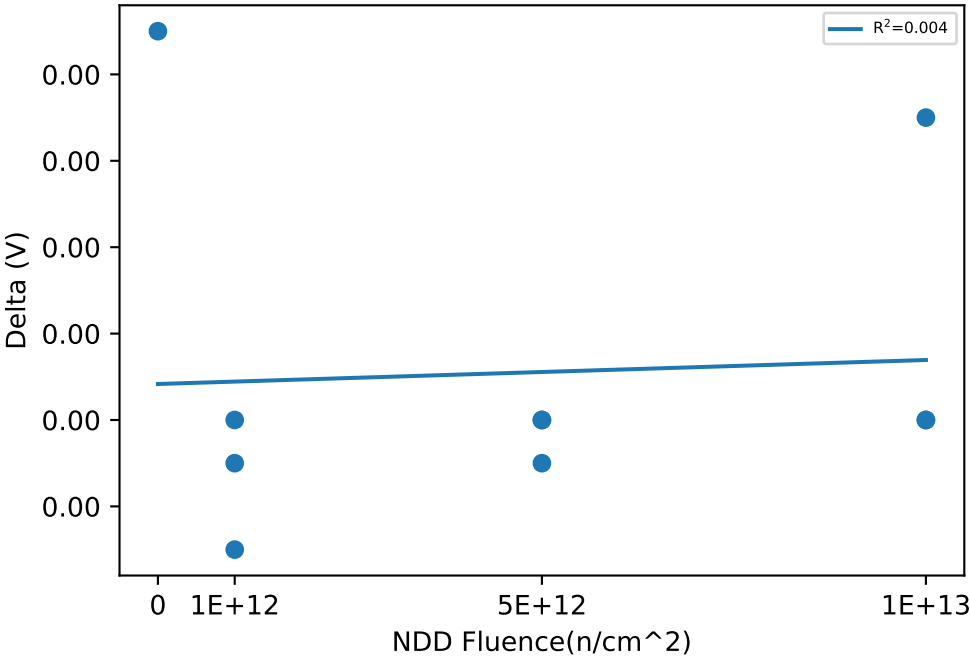
NDD vs Result Stats



Test Results (Upper Limit = 0.15 (V))

Serial #	Fluence(n/cm ²)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	0.0685	0.069	0.0005
551	1e+12	NDD	0.0675	0.0678	0.0003
552	1e+12	NDD	0.0681	0.0687	0.0006
553	5e+12	NDD	0.0679	0.0684	0.0005
554	5e+12	NDD	0.068	0.0686	0.0006
555	5e+12	NDD	0.0671	0.0677	0.0006
556	1e+13	NDD	0.0677	0.0683	0.0006
557	1e+13	NDD	0.0673	0.0679	0.0006
558	1e+13	NDD	0.067	0.0683	0.0013
559	0	NDD, Ctrl	0.0674	0.0689	0.0015

NDD vs Post - Pre Exposure Delta

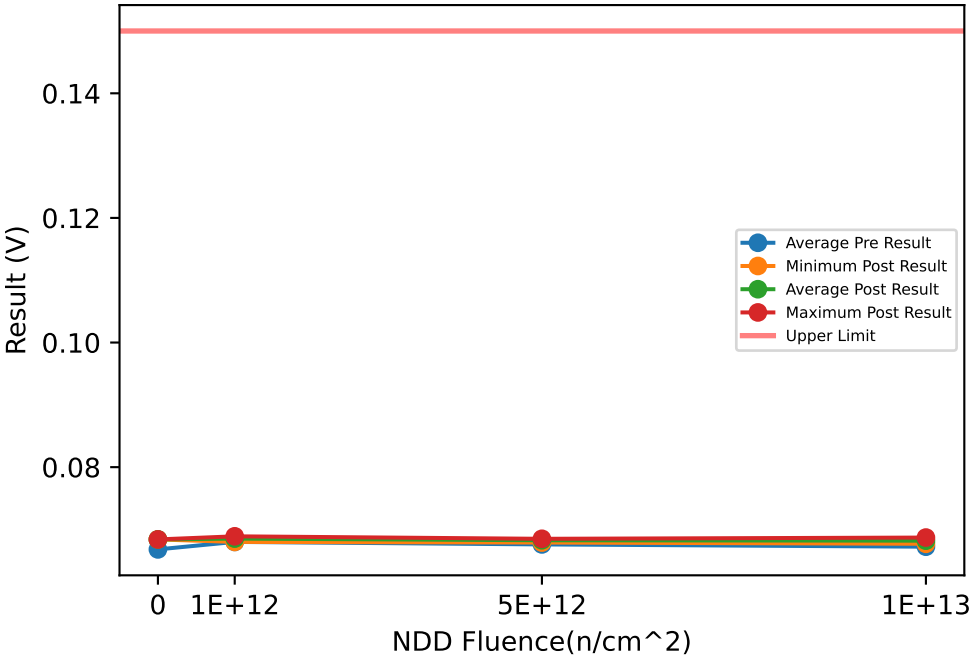


Test Statistics (V)

Fluence(n/cm ²)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0674	0.0674	0.0674		0.0689	0.0689	0.0689		0.0015	0.0015	0.0015	
1e+12	0.0675	0.068033	0.0685	0.00050332	0.0678	0.0685	0.069	0.0006245	0.0003	0.00046667	0.0006	0.00015275
5e+12	0.0671	0.067667	0.068	0.00049329	0.0677	0.068233	0.0686	0.00047258	0.0005	0.00056667	0.0006	5.7735e-05
1e+13	0.067	0.067333	0.0677	0.00035119	0.0679	0.068167	0.0683	0.00023094	0.0006	0.00083333	0.0013	0.00040415

Device Test: 47.1 V_HS_OL(VOL HO VIN_14V)

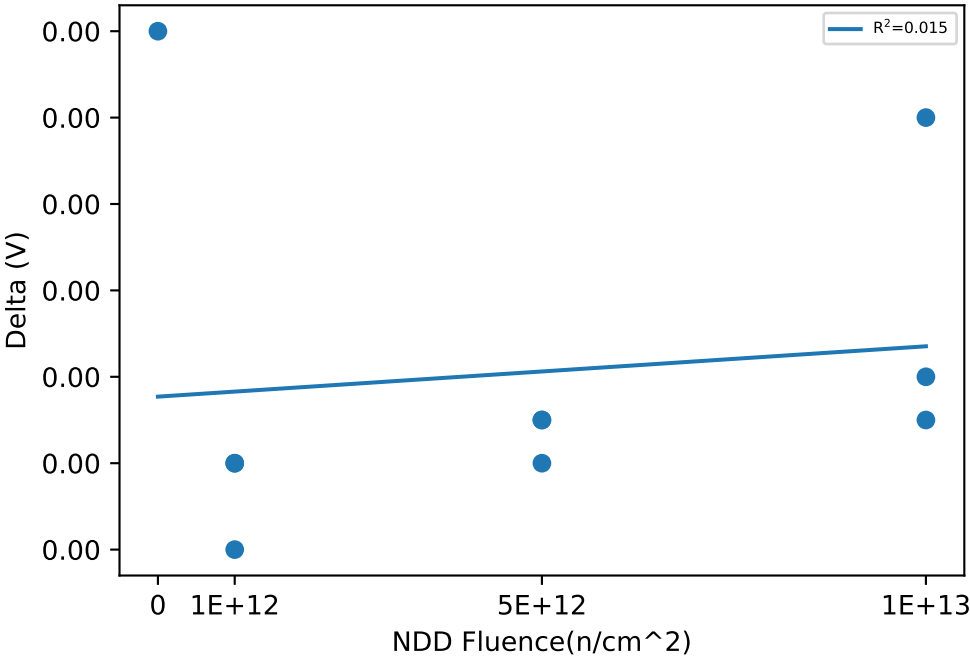
NDD vs Result Stats



Test Results (Upper Limit = 0.15 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	0.0683	0.0689	0.0006
551	1e+12	NDD	0.0676	0.068	0.0004
552	1e+12	NDD	0.0681	0.0687	0.0006
553	5e+12	NDD	0.0677	0.0684	0.0007
554	5e+12	NDD	0.0678	0.0685	0.0007
555	5e+12	NDD	0.0673	0.0679	0.0006
556	1e+13	NDD	0.0675	0.0682	0.0007
557	1e+13	NDD	0.0669	0.0677	0.0008
558	1e+13	NDD	0.0673	0.0687	0.0014
559	0	NDD, Ctrl	0.0668	0.0684	0.0016

NDD vs Post - Pre Exposure Delta

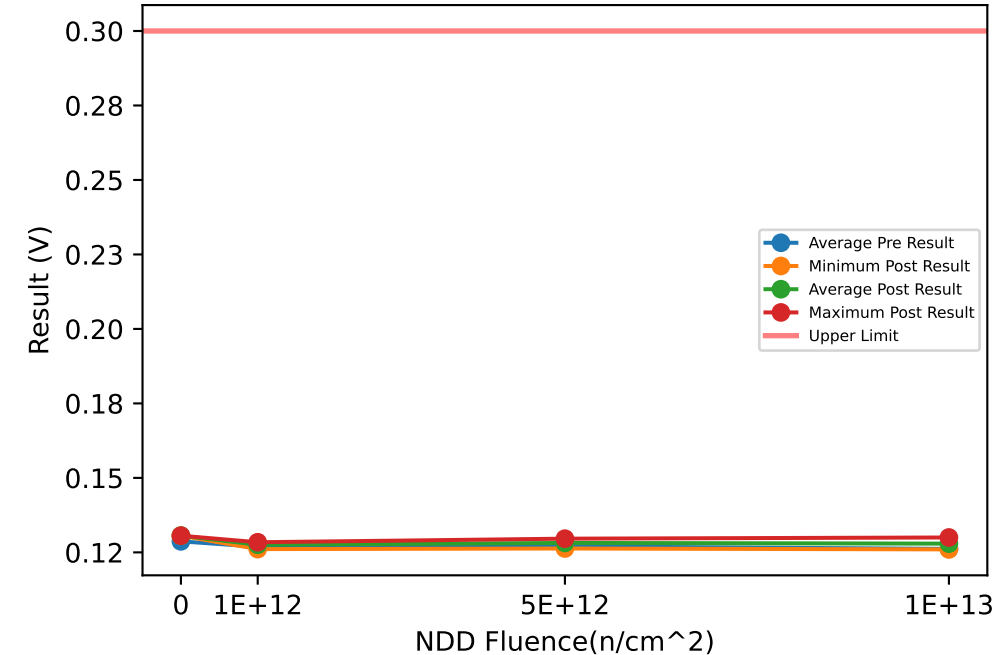


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0668	0.0668	0.0668		0.0684	0.0684	0.0684		0.0016	0.0016	0.0016	
1e+12	0.0676	0.068	0.0683	0.00036056	0.068	0.068533	0.0689	0.00047258	0.0004	0.00053333	0.0006	0.00011547
5e+12	0.0673	0.0676	0.0678	0.00026458	0.0679	0.068267	0.0685	0.00032146	0.0006	0.00066667	0.0007	5.7735e-05
1e+13	0.0669	0.067233	0.0675	0.00030551	0.0677	0.0682	0.0687	0.0005	0.0007	0.00096667	0.0014	0.00037859

Device Test: 47.2 V_LS_OH_DELTA(VOH Delta LO VIN_14V)

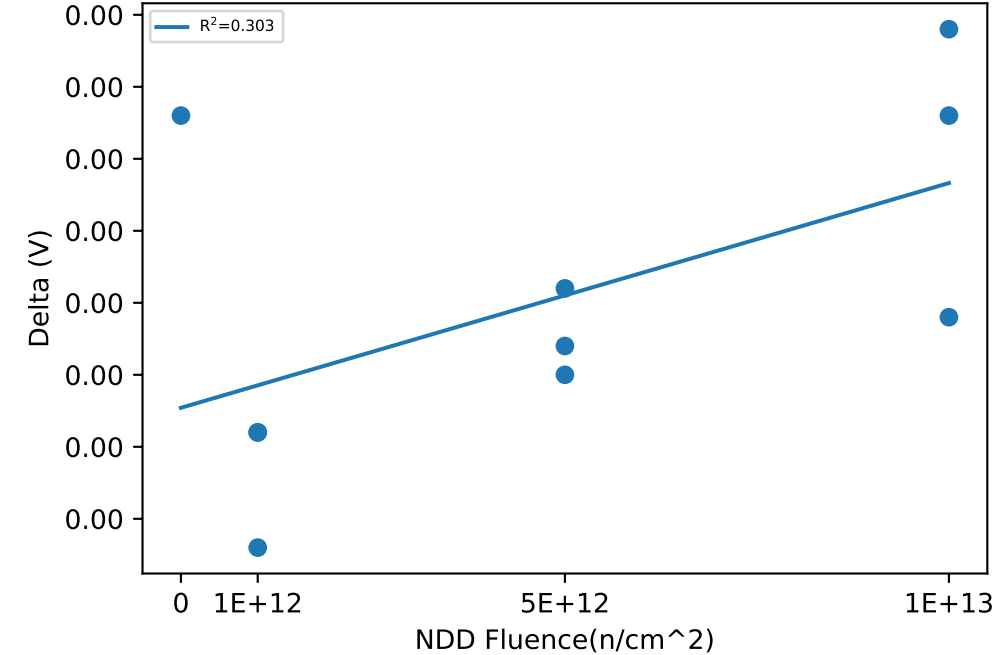
NDD vs Result Stats



Test Results (Upper Limit = 0.3 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	0.128	0.1284	0.0004
551	1e+12	NDD	0.1253	0.1261	0.0008
552	1e+12	NDD	0.1274	0.1282	0.0008
553	5e+12	NDD	0.1275	0.1286	0.0011
554	5e+12	NDD	0.1286	0.1296	0.001
555	5e+12	NDD	0.125	0.1263	0.0013
556	1e+13	NDD	0.1248	0.126	0.0012
557	1e+13	NDD	0.1259	0.1278	0.0019
558	1e+13	NDD	0.1278	0.13	0.0022
559	0	NDD, Ctrl	0.1287	0.1306	0.0019

NDD vs Post - Pre Exposure Delta

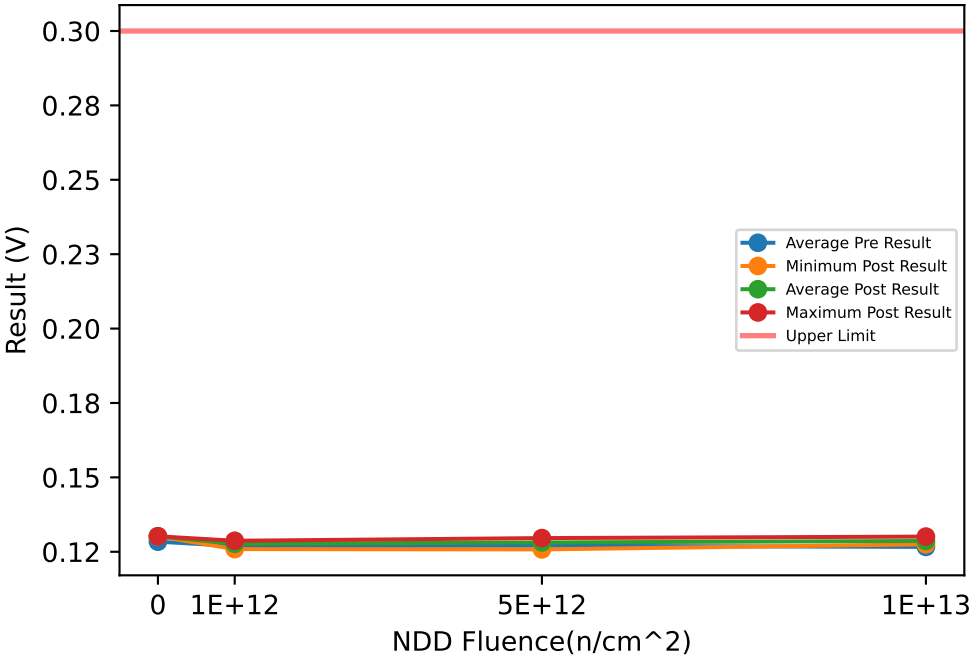


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1287	0.1287	0.1287		0.1306	0.1306	0.1306		0.0019	0.0019	0.0019	
1e+12	0.1253	0.1269	0.128	0.0014177	0.1261	0.12757	0.1284	0.0012741	0.0004	0.00066667	0.0008	0.00023094
5e+12	0.125	0.12703	0.1286	0.0018448	0.1263	0.12817	0.1296	0.0016921	0.001	0.0011333	0.0013	0.00015275
1e+13	0.1248	0.12617	0.1278	0.0015177	0.126	0.12793	0.13	0.0020033	0.0012	0.0017667	0.0022	0.00051316

Device Test: 47.3 V_HS_OH_DELTA(VOH Delta HO VIN_14V)

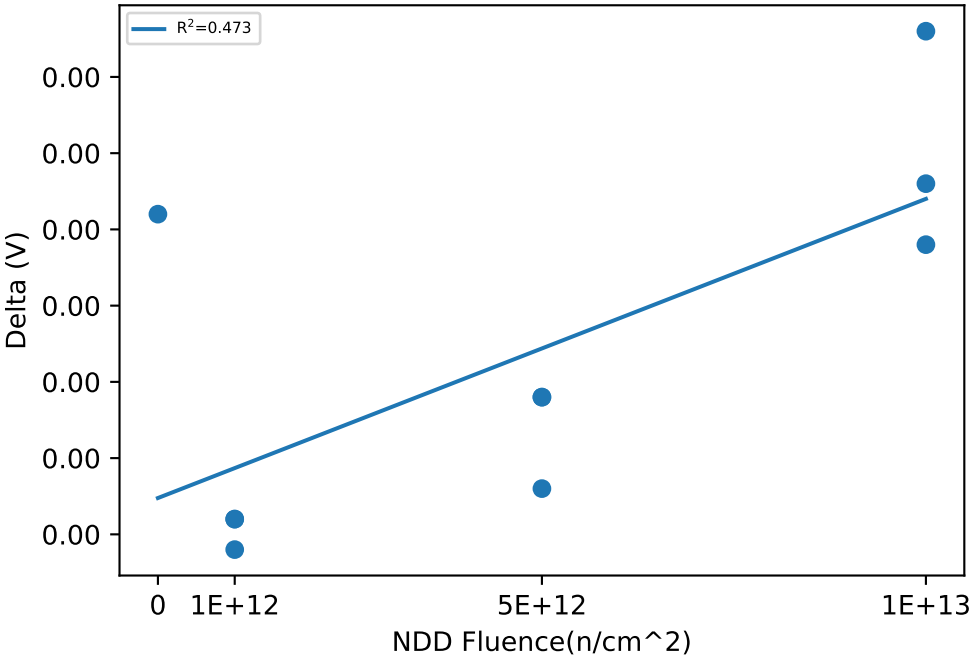
NDD vs Result Stats



Test Results (Upper Limit = 0.3 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	0.1277	0.1285	0.0008
551	1e+12	NDD	0.1251	0.1259	0.0008
552	1e+12	NDD	0.128	0.1287	0.0007
553	5e+12	NDD	0.1284	0.1296	0.0012
554	5e+12	NDD	0.1278	0.129	0.0012
555	5e+12	NDD	0.1249	0.1258	0.0009
556	1e+13	NDD	0.1258	0.1275	0.0017
557	1e+13	NDD	0.1264	0.1283	0.0019
558	1e+13	NDD	0.1277	0.1301	0.0024
559	0	NDD, Ctrl	0.1284	0.1302	0.0018

NDD vs Post - Pre Exposure Delta

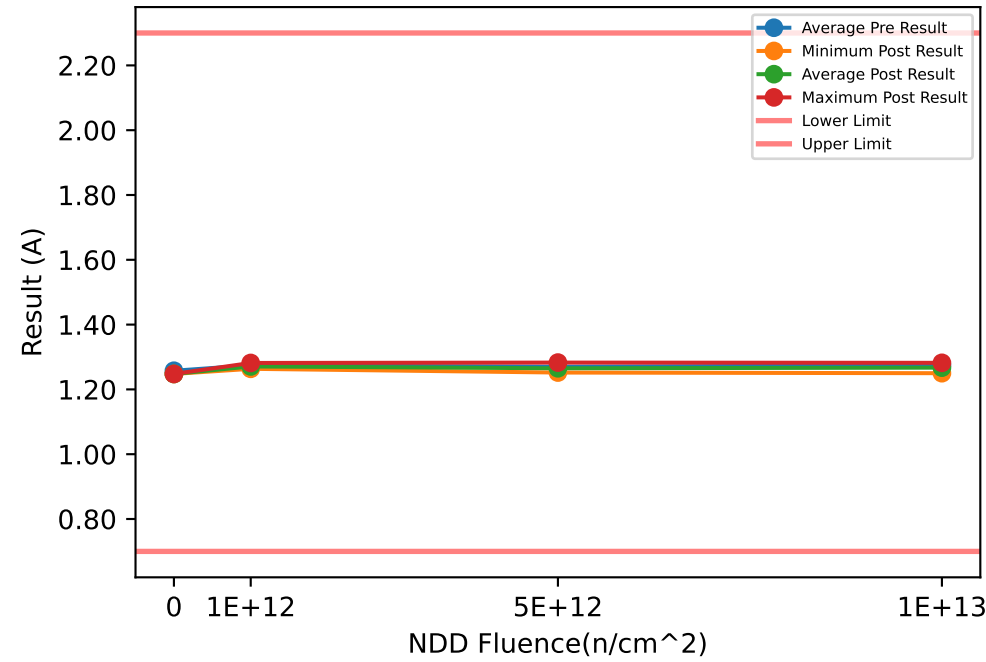


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1284	0.1284	0.1284		0.1302	0.1302	0.1302		0.0018	0.0018	0.0018	
1e+12	0.1251	0.12693	0.128	0.0015948	0.1259	0.1277	0.1287	0.001562	0.0007	0.00076667	0.0008	5.7735e-05
5e+12	0.1249	0.12703	0.1284	0.0018717	0.1258	0.12813	0.1296	0.0020429	0.0009	0.0011	0.0012	0.00017321
1e+13	0.1258	0.12663	0.1277	0.00097125	0.1275	0.12863	0.1301	0.0013317	0.0017	0.002	0.0024	0.00036056

Device Test: 50.0 I_LS_OH(IOH LO VIN_10V)

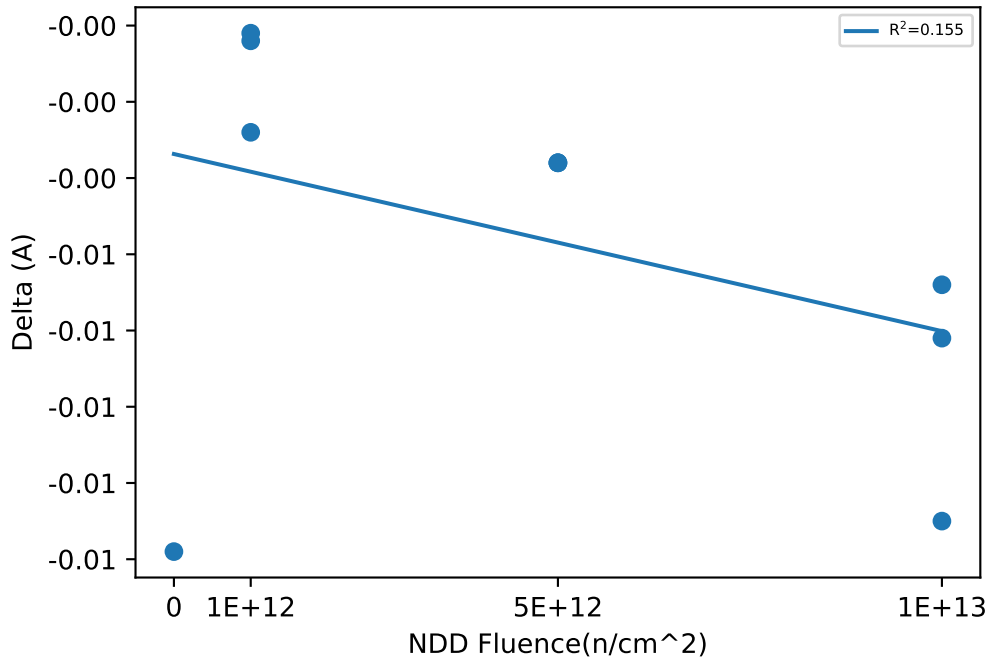
NDD vs Result Stats



Test Results (Lower Limit = 0.7, Upper Limit = 2.3 (A))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	1.2666	1.2635	-0.0031
551	1e+12	NDD	1.2848	1.2816	-0.0032
552	1e+12	NDD	1.2718	1.2674	-0.0044
553	5e+12	NDD	1.2655	1.2607	-0.0048
554	5e+12	NDD	1.2568	1.252	-0.0048
555	5e+12	NDD	1.2876	1.2828	-0.0048
556	1e+13	NDD	1.2884	1.282	-0.0064
557	1e+13	NDD	1.2765	1.2694	-0.0071
558	1e+13	NDD	1.2595	1.25	-0.0095
559	0	NDD, Ctrl	1.2576	1.2477	-0.0099

NDD vs Post - Pre Exposure Delta

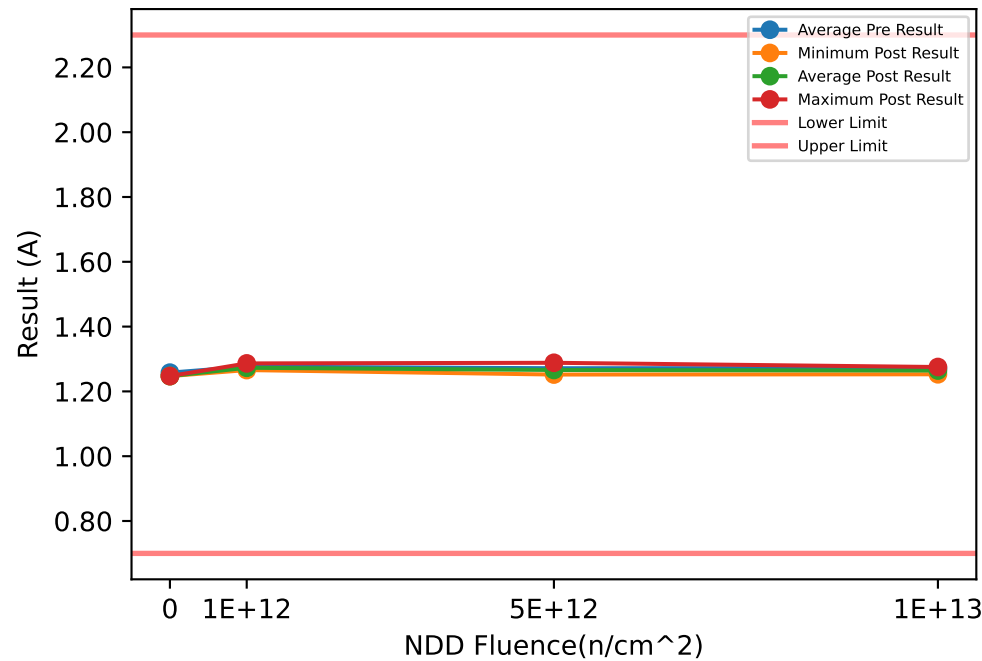


Test Statistics (A)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2576	1.2576	1.2576		1.2477	1.2477	1.2477		-0.0099	-0.0099	-0.0099	
1e+12	1.2666	1.2744	1.2848	0.0093744	1.2635	1.2708	1.2816	0.0095259	-0.0044	-0.0035667	-0.0031	0.00072342
5e+12	1.2568	1.27	1.2876	0.015878	1.252	1.2652	1.2828	0.015878	-0.0048	-0.0048	-0.0048	1.2813e-16
1e+13	1.2595	1.2748	1.2884	0.014525	1.25	1.2671	1.282	0.01612	-0.0095	-0.0076667	-0.0064	0.0016258

Device Test: 50.1 I_HS_OH(IOH HO VIN_10V)

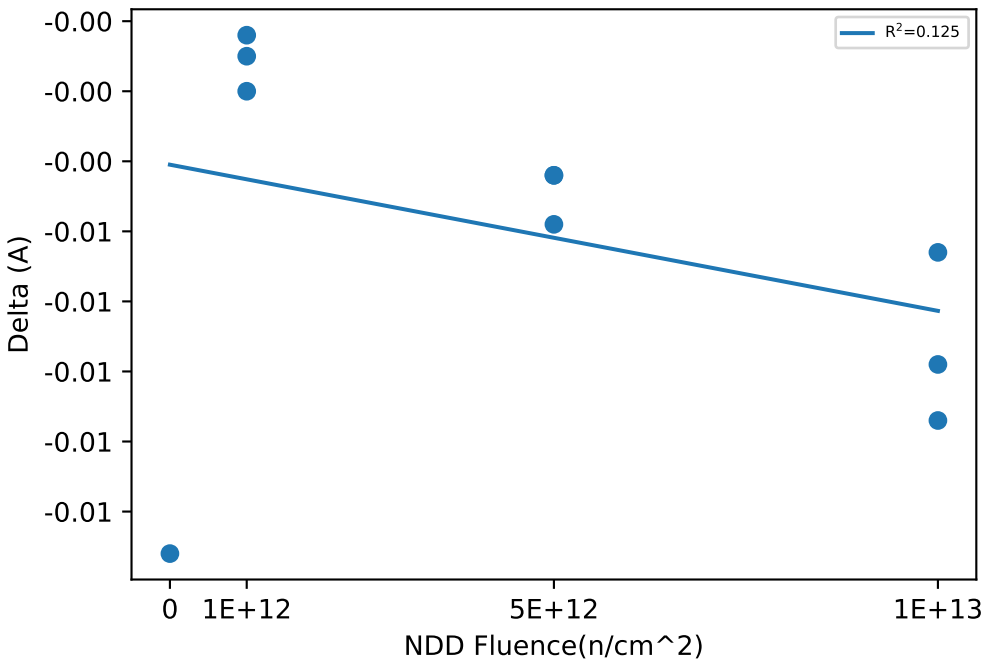
NDD vs Result Stats



Test Results (Lower Limit = 0.7, Upper Limit = 2.3 (A))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	1.269	1.2658	-0.0032
551	1e+12	NDD	1.2899	1.2864	-0.0035
552	1e+12	NDD	1.2706	1.2666	-0.004
553	5e+12	NDD	1.2579	1.252	-0.0059
554	5e+12	NDD	1.2631	1.2579	-0.0052
555	5e+12	NDD	1.2935	1.2883	-0.0052
556	1e+13	NDD	1.2816	1.2753	-0.0063
557	1e+13	NDD	1.2729	1.265	-0.0079
558	1e+13	NDD	1.2615	1.2528	-0.0087
559	0	NDD, Ctrl	1.2579	1.2473	-0.0106

NDD vs Post - Pre Exposure Delta

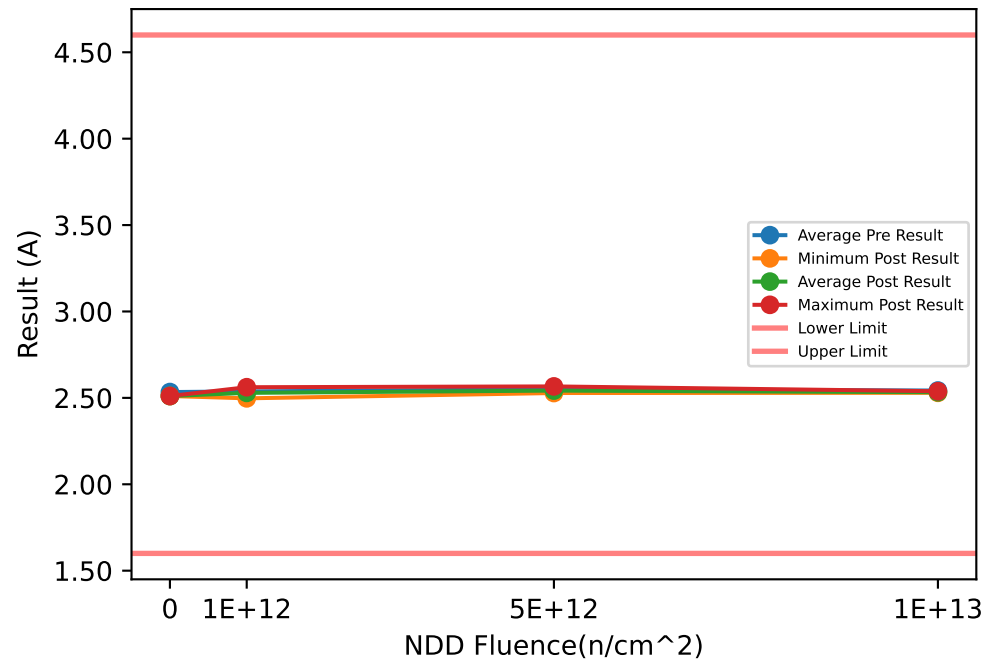


Test Statistics (A)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2579	1.2579	1.2579		1.2473	1.2473	1.2473		-0.0106	-0.0106	-0.0106	
1e+12	1.269	1.2765	1.2899	0.011632	1.2658	1.2729	1.2864	0.011669	-0.004	-0.0035667	-0.0032	0.00040415
5e+12	1.2579	1.2715	1.2935	0.019229	1.252	1.2661	1.2883	0.019479	-0.0059	-0.0054333	-0.0052	0.00040415
1e+13	1.2615	1.272	1.2816	0.01008	1.2528	1.2644	1.2753	0.011263	-0.0087	-0.0076333	-0.0063	0.001222

Device Test: 50.2 I_LS_OL(IOL LO VIN_10V)

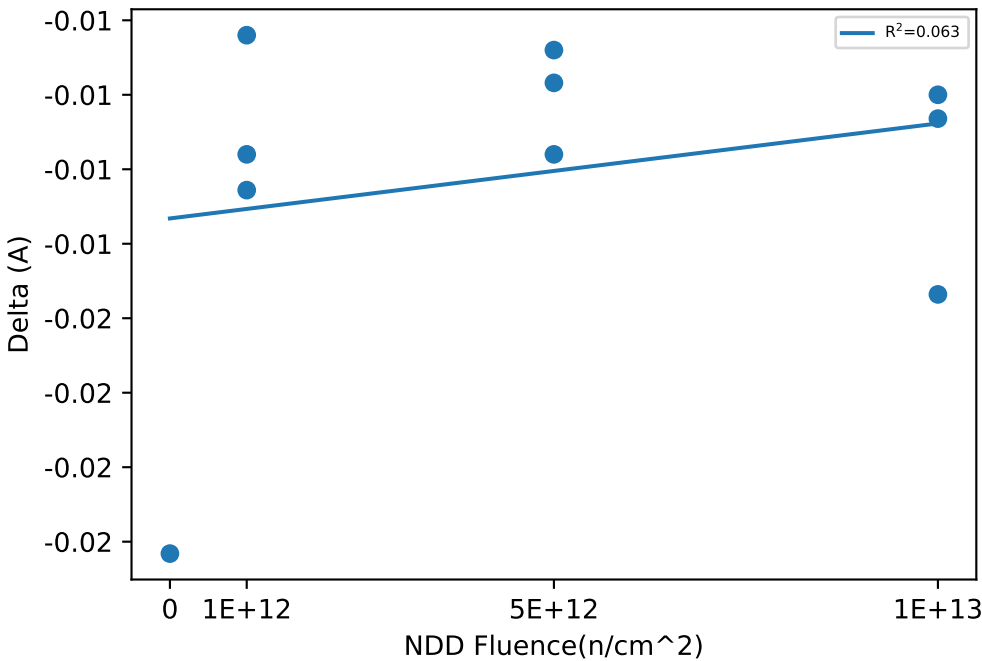
NDD vs Result Stats



Test Results (Lower Limit = 1.6, Upper Limit = 4.6 (A))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	2.5068	2.4973	-0.0095
551	1e+12	NDD	2.5672	2.5617	-0.0055
552	1e+12	NDD	2.5384	2.5277	-0.0107
553	5e+12	NDD	2.5376	2.5281	-0.0095
554	5e+12	NDD	2.5392	2.5321	-0.0071
555	5e+12	NDD	2.5724	2.5664	-0.006
556	1e+13	NDD	2.5376	2.5301	-0.0075
557	1e+13	NDD	2.5376	2.5293	-0.0083
558	1e+13	NDD	2.5526	2.5384	-0.0142
559	0	NDD, Ctrl	2.5337	2.5108	-0.0229

NDD vs Post - Pre Exposure Delta

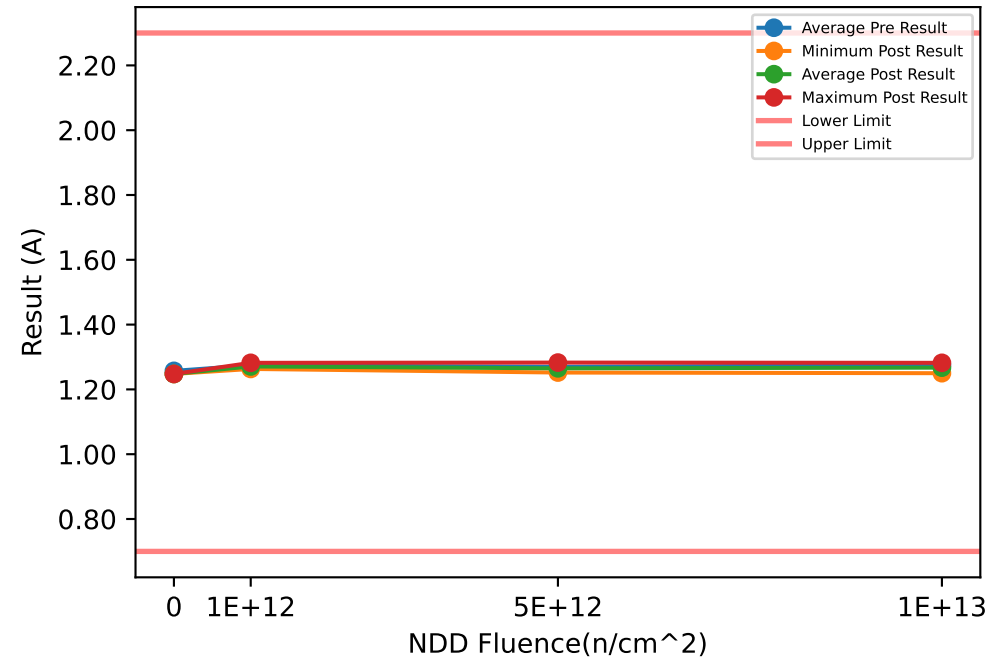


Test Statistics (A)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.5337	2.5337	2.5337		2.5108	2.5108	2.5108		-0.0229	-0.0229	-0.0229	
1e+12	2.5068	2.5375	2.5672	0.030211	2.4973	2.5289	2.5617	0.032217	-0.0107	-0.0085667	-0.0055	0.0027227
5e+12	2.5376	2.5497	2.5724	0.019646	2.5281	2.5422	2.5664	0.021053	-0.0095	-0.0075333	-0.006	0.0017898
1e+13	2.5376	2.5426	2.5526	0.0086603	2.5293	2.5326	2.5384	0.0050388	-0.0142	-0.01	-0.0075	0.0036592

Device Test: 51.0 I_LS_OH(IOH LO VIN_12V)

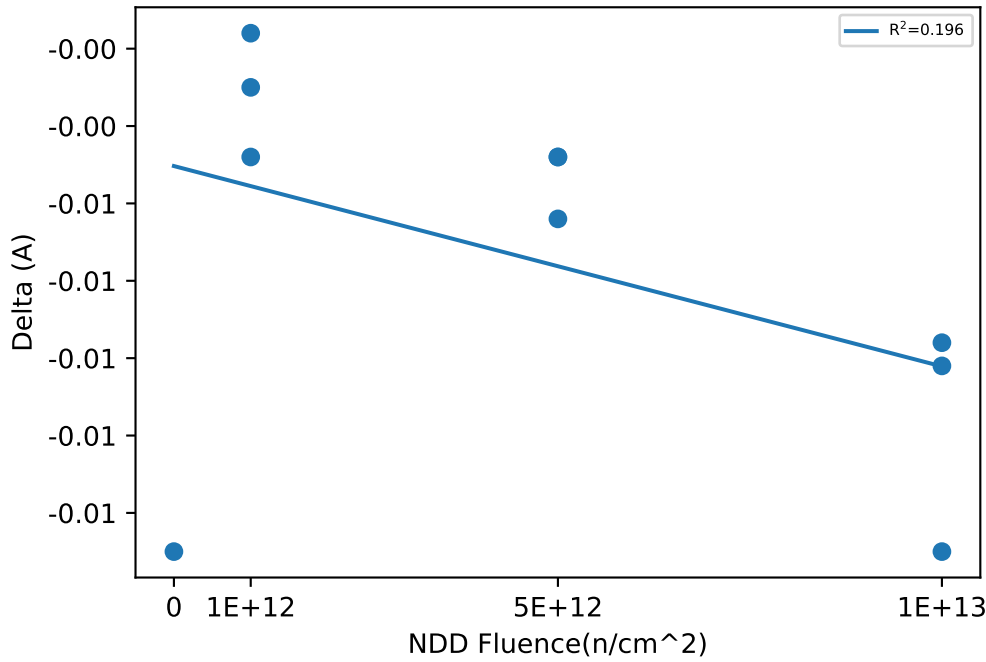
NDD vs Result Stats



Test Results (Lower Limit = 0.7, Upper Limit = 2.3 (A))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	1.2666	1.2631	-0.0035
551	1e+12	NDD	1.2848	1.282	-0.0028
552	1e+12	NDD	1.2718	1.2674	-0.0044
553	5e+12	NDD	1.2655	1.2603	-0.0052
554	5e+12	NDD	1.2564	1.252	-0.0044
555	5e+12	NDD	1.2872	1.2828	-0.0044
556	1e+13	NDD	1.2888	1.282	-0.0068
557	1e+13	NDD	1.2765	1.2694	-0.0071
558	1e+13	NDD	1.2595	1.25	-0.0095
559	0	NDD, Ctrl	1.2572	1.2477	-0.0095

NDD vs Post - Pre Exposure Delta

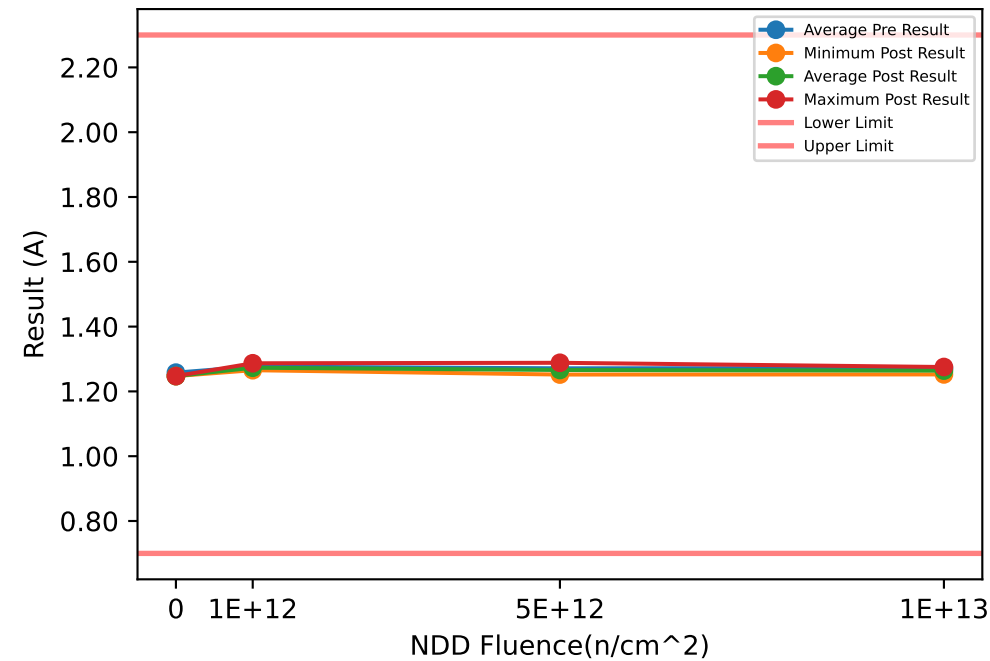


Test Statistics (A)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2572	1.2572	1.2572		1.2477	1.2477	1.2477		-0.0095	-0.0095	-0.0095	
1e+12	1.2666	1.2744	1.2848	0.0093744	1.2631	1.2708	1.282	0.0099067	-0.0044	-0.0035667	-0.0028	0.00080208
5e+12	1.2564	1.2697	1.2872	0.015824	1.252	1.265	1.2828	0.015936	-0.0052	-0.0046667	-0.0044	0.00046188
1e+13	1.2595	1.2749	1.2888	0.014713	1.25	1.2671	1.282	0.01612	-0.0095	-0.0078	-0.0068	0.0014799

Device Test: 51.1 I_HS_OH(IOH HO VIN_12V)

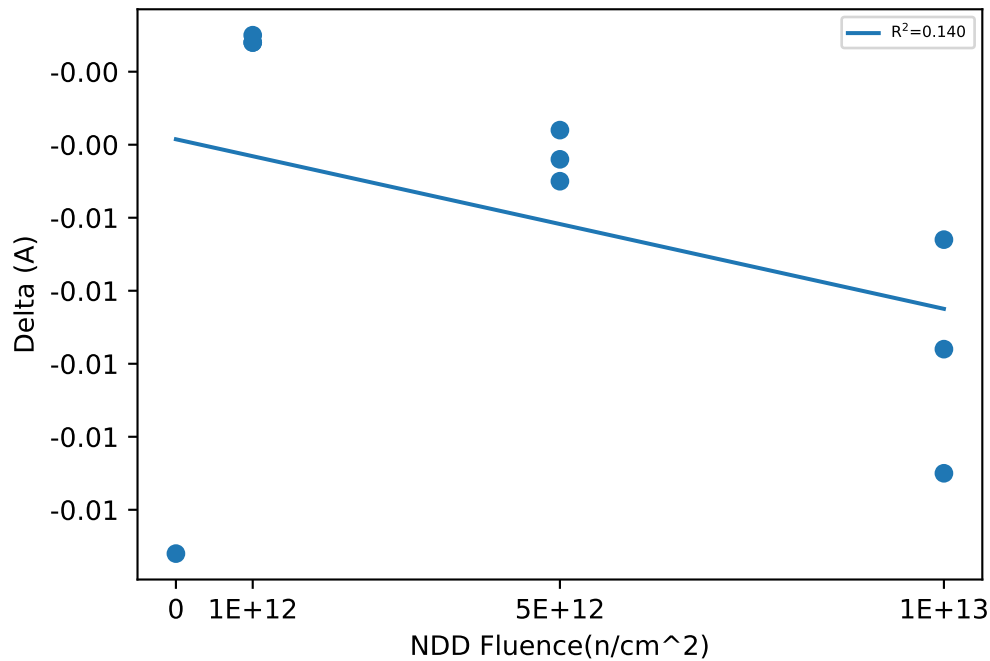
NDD vs Result Stats



Test Results (Lower Limit = 0.7, Upper Limit = 2.3 (A))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	1.269	1.2654	-0.0036
551	1e+12	NDD	1.2903	1.2868	-0.0035
552	1e+12	NDD	1.2706	1.267	-0.0036
553	5e+12	NDD	1.2575	1.252	-0.0055
554	5e+12	NDD	1.2631	1.2579	-0.0052
555	5e+12	NDD	1.2931	1.2883	-0.0048
556	1e+13	NDD	1.2816	1.2753	-0.0063
557	1e+13	NDD	1.2725	1.2647	-0.0078
558	1e+13	NDD	1.2619	1.2524	-0.0095
559	0	NDD, Ctrl	1.2579	1.2473	-0.0106

NDD vs Post - Pre Exposure Delta

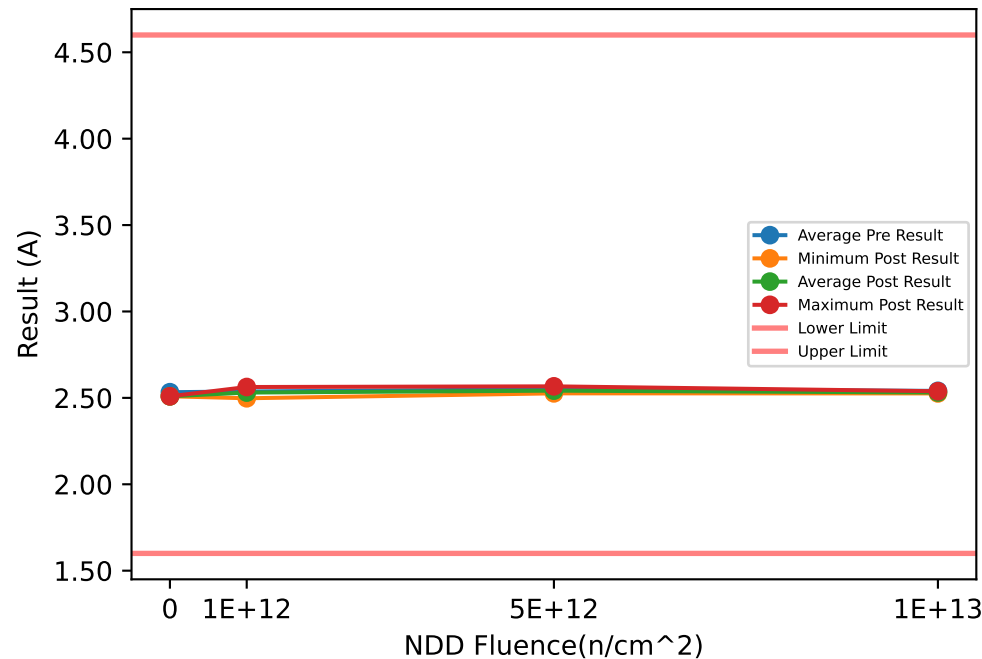


Test Statistics (A)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2579	1.2579	1.2579		1.2473	1.2473	1.2473		-0.0106	-0.0106	-0.0106	
1e+12	1.269	1.2766	1.2903	0.011863	1.2654	1.2731	1.2868	0.01192	-0.0036	-0.0035667	-0.0035	5.7735e-05
5e+12	1.2575	1.2712	1.2931	0.019143	1.252	1.2661	1.2883	0.019479	-0.0055	-0.0051667	-0.0048	0.00035119
1e+13	1.2619	1.272	1.2816	0.0098595	1.2524	1.2641	1.2753	0.011461	-0.0095	-0.0078667	-0.0063	0.001601

Device Test: 51.2 I_LS_OL(IOL LO VIN_12V)

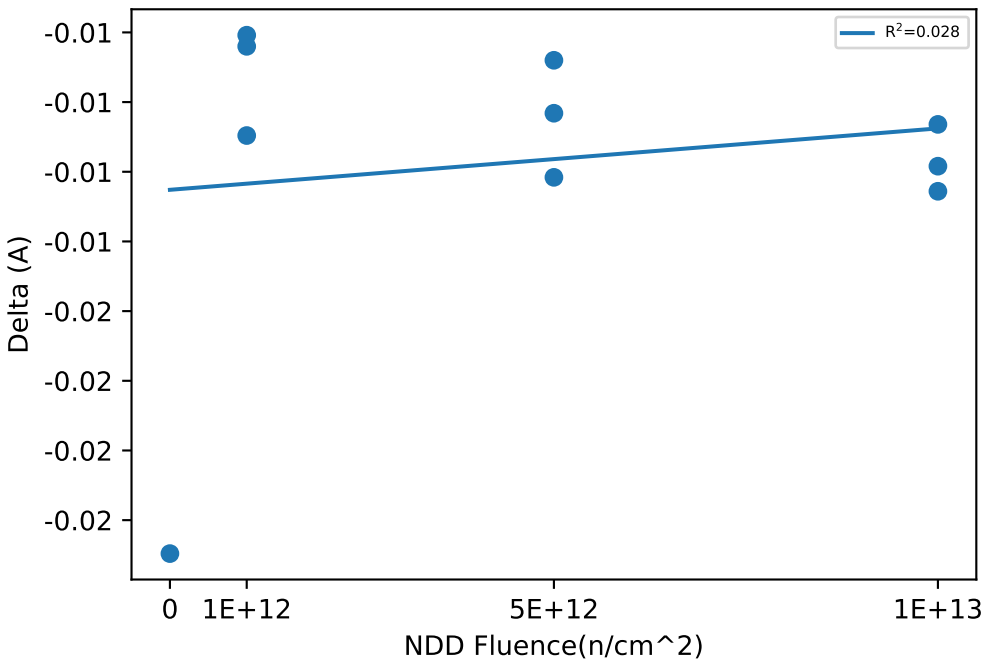
NDD vs Result Stats



Test Results (Lower Limit = 1.6, Upper Limit = 4.6 (A))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	2.5064	2.4977	-0.0087
551	1e+12	NDD	2.5684	2.5629	-0.0055
552	1e+12	NDD	2.5364	2.5313	-0.0051
553	5e+12	NDD	2.5364	2.5262	-0.0102
554	5e+12	NDD	2.5404	2.5325	-0.0079
555	5e+12	NDD	2.5728	2.5668	-0.006
556	1e+13	NDD	2.5372	2.5289	-0.0083
557	1e+13	NDD	2.5356	2.5258	-0.0098
558	1e+13	NDD	2.5491	2.5384	-0.0107
559	0	NDD, Ctrl	2.5329	2.5092	-0.0237

NDD vs Post - Pre Exposure Delta

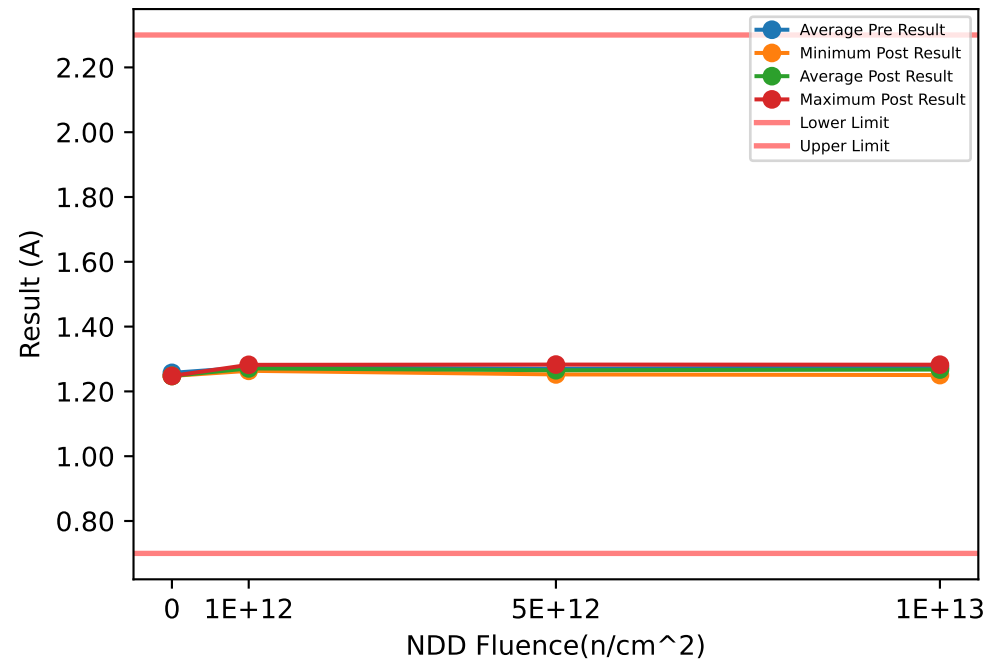


Test Statistics (A)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.5329	2.5329	2.5329		2.5092	2.5092	2.5092		-0.0237	-0.0237	-0.0237	
1e+12	2.5064	2.5371	2.5684	0.031005	2.4977	2.5306	2.5629	0.032605	-0.0087	-0.0064333	-0.0051	0.0019732
5e+12	2.5364	2.5499	2.5728	0.019961	2.5262	2.5418	2.5668	0.02185	-0.0102	-0.0080333	-0.006	0.0021032
1e+13	2.5356	2.5406	2.5491	0.0073759	2.5258	2.531	2.5384	0.0065653	-0.0107	-0.0096	-0.0083	0.0012124

Device Test: 52.0 I_LS_OH(IOH LO VIN_14V)

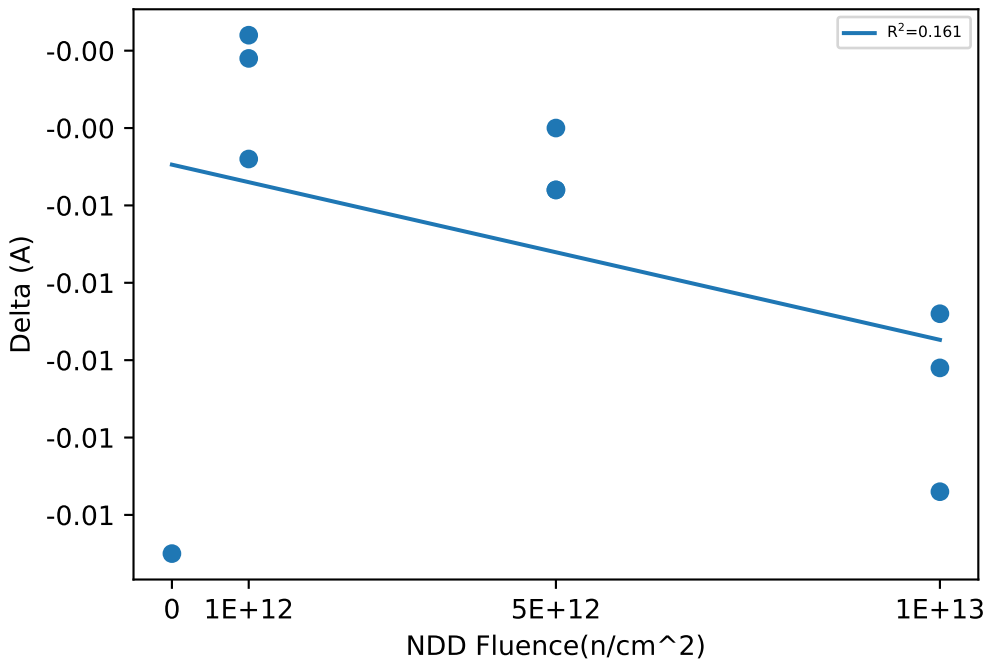
NDD vs Result Stats



Test Results (Lower Limit = 0.7, Upper Limit = 2.3 (A))

Serial #	Fluence(n/cm ²)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	1.2666	1.2635	-0.0031
551	1e+12	NDD	1.2848	1.282	-0.0028
552	1e+12	NDD	1.2718	1.2674	-0.0044
553	5e+12	NDD	1.2655	1.2607	-0.0048
554	5e+12	NDD	1.2564	1.2524	-0.004
555	5e+12	NDD	1.2876	1.2828	-0.0048
556	1e+13	NDD	1.2888	1.2824	-0.0064
557	1e+13	NDD	1.2765	1.2694	-0.0071
558	1e+13	NDD	1.2591	1.2504	-0.0087
559	0	NDD, Ctrl	1.2572	1.2477	-0.0095

NDD vs Post - Pre Exposure Delta

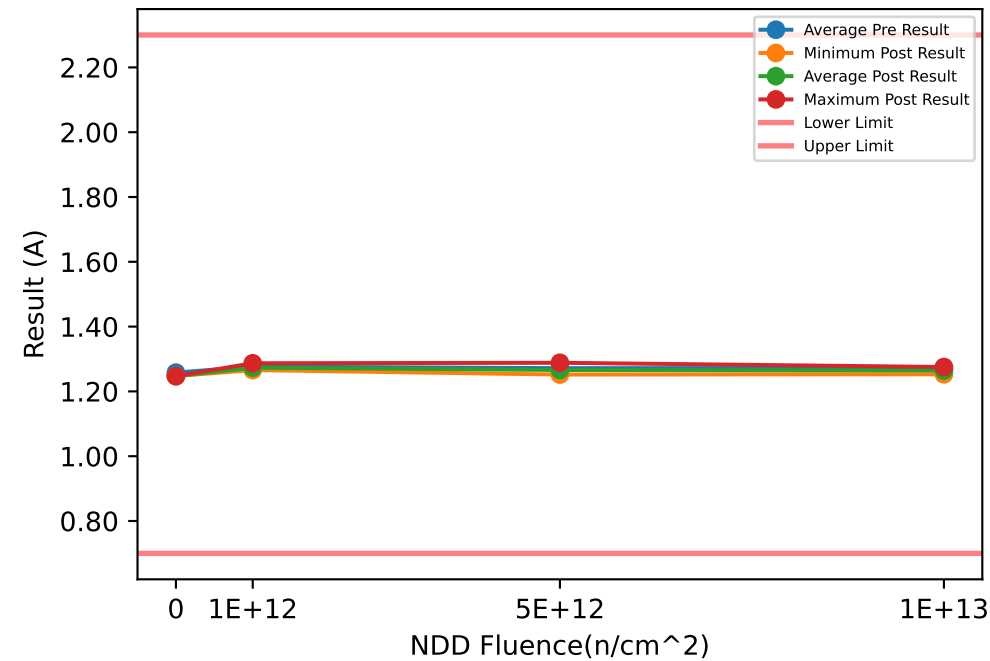


Test Statistics (A)

Fluence(n/cm ²)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2572	1.2572	1.2572		1.2477	1.2477	1.2477		-0.0095	-0.0095	-0.0095	
1e+12	1.2666	1.2744	1.2848	0.0093744	1.2635	1.271	1.282	0.0097521	-0.0044	-0.0034333	-0.0028	0.00085049
5e+12	1.2564	1.2698	1.2876	0.016045	1.2524	1.2653	1.2828	0.015713	-0.0048	-0.0045333	-0.004	0.00046188
1e+13	1.2591	1.2748	1.2888	0.014923	1.2504	1.2674	1.2824	0.016093	-0.0087	-0.0074	-0.0064	0.001179

Device Test: 52.1 I_HS_OH(IOH HO VIN_14V)

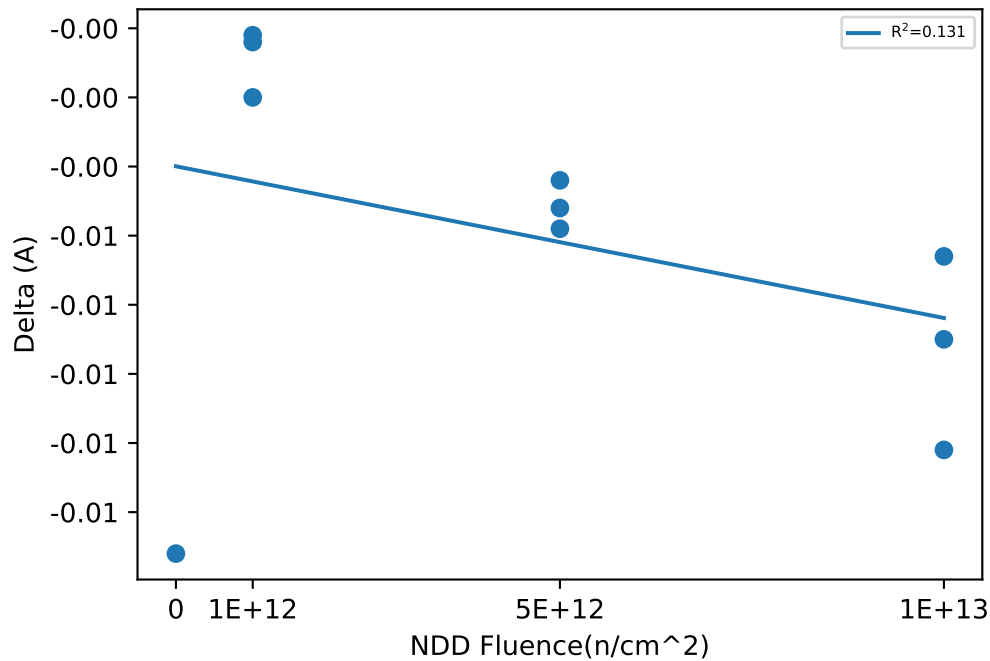
NDD vs Result Stats



Test Results (Lower Limit = 0.7, Upper Limit = 2.3 (A))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	1.269	1.2658	-0.0032
551	1e+12	NDD	1.2899	1.2868	-0.0031
552	1e+12	NDD	1.271	1.267	-0.004
553	5e+12	NDD	1.2579	1.252	-0.0059
554	5e+12	NDD	1.2631	1.2579	-0.0052
555	5e+12	NDD	1.2939	1.2883	-0.0056
556	1e+13	NDD	1.2816	1.2753	-0.0063
557	1e+13	NDD	1.2725	1.265	-0.0075
558	1e+13	NDD	1.2619	1.2528	-0.0091
559	0	NDD, Ctrl	1.2579	1.2473	-0.0106

NDD vs Post - Pre Exposure Delta

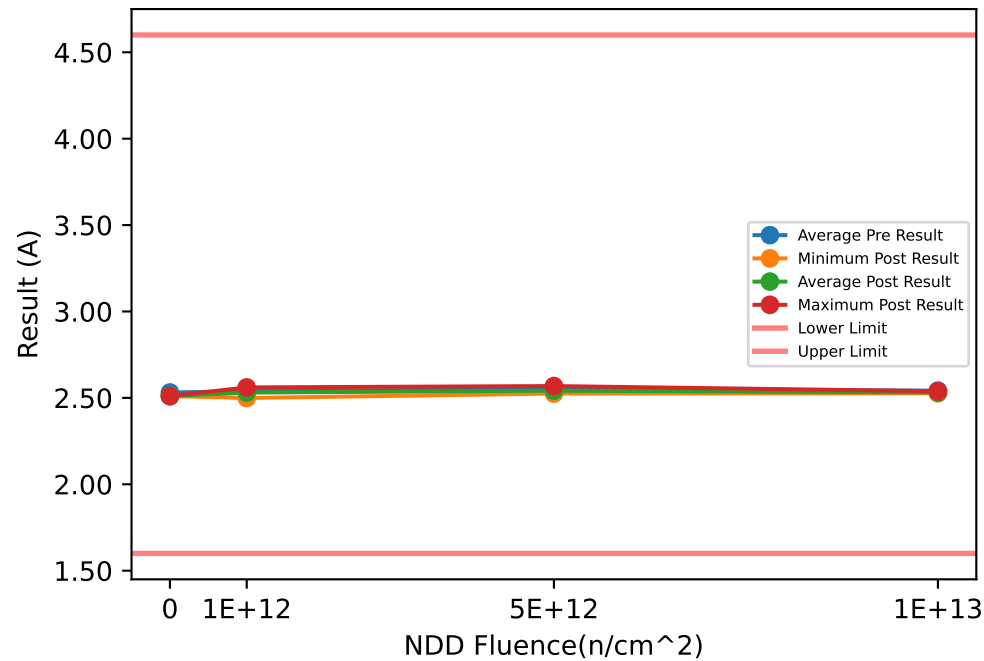


Test Statistics (A)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2579	1.2579	1.2579		1.2473	1.2473	1.2473		-0.0106	-0.0106	-0.0106	
1e+12	1.269	1.2766	1.2899	0.011533	1.2658	1.2732	1.2868	0.011793	-0.004	-0.0034333	-0.0031	0.00049329
5e+12	1.2579	1.2716	1.2939	0.019458	1.252	1.2661	1.2883	0.019479	-0.0059	-0.0055667	-0.0052	0.00035119
1e+13	1.2619	1.272	1.2816	0.0098595	1.2528	1.2644	1.2753	0.011263	-0.0091	-0.0076333	-0.0063	0.0014048

Device Test: 52.2 I_LS_OL(IOL LO VIN_14V)

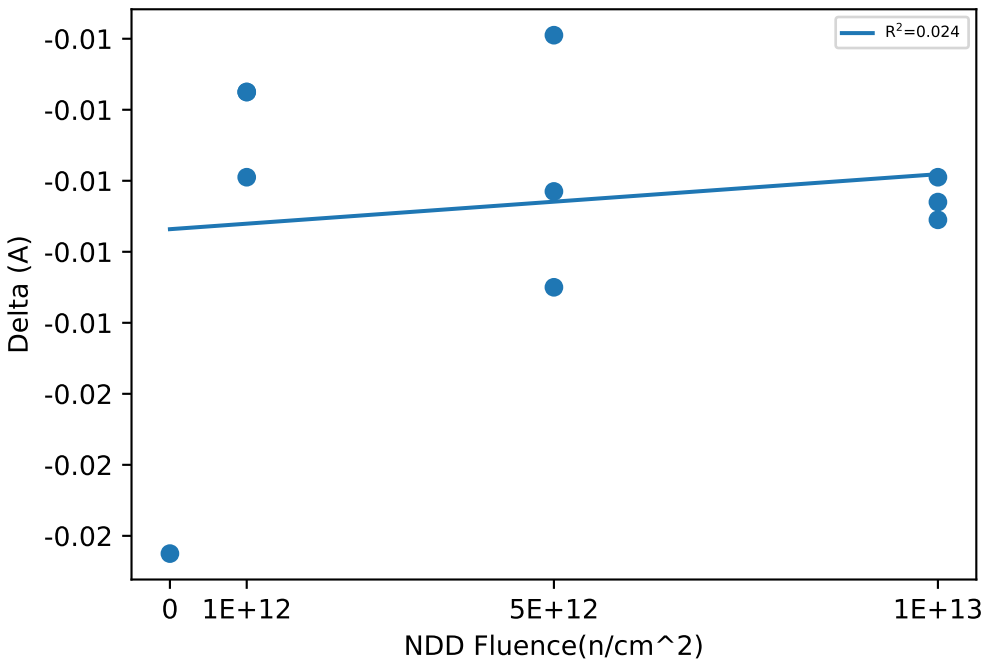
NDD vs Result Stats



Test Results (Lower Limit = 1.6, Upper Limit = 4.6 (A))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	2.5068	2.4993	-0.0075
551	1e+12	NDD	2.5704	2.5605	-0.0099
552	1e+12	NDD	2.5392	2.5317	-0.0075
553	5e+12	NDD	2.538	2.525	-0.013
554	5e+12	NDD	2.542	2.5317	-0.0103
555	5e+12	NDD	2.5743	2.5684	-0.0059
556	1e+13	NDD	2.5372	2.5266	-0.0106
557	1e+13	NDD	2.5388	2.5289	-0.0099
558	1e+13	NDD	2.5495	2.5384	-0.0111
559	0	NDD, Ctrl	2.5309	2.5104	-0.0205

NDD vs Post - Pre Exposure Delta

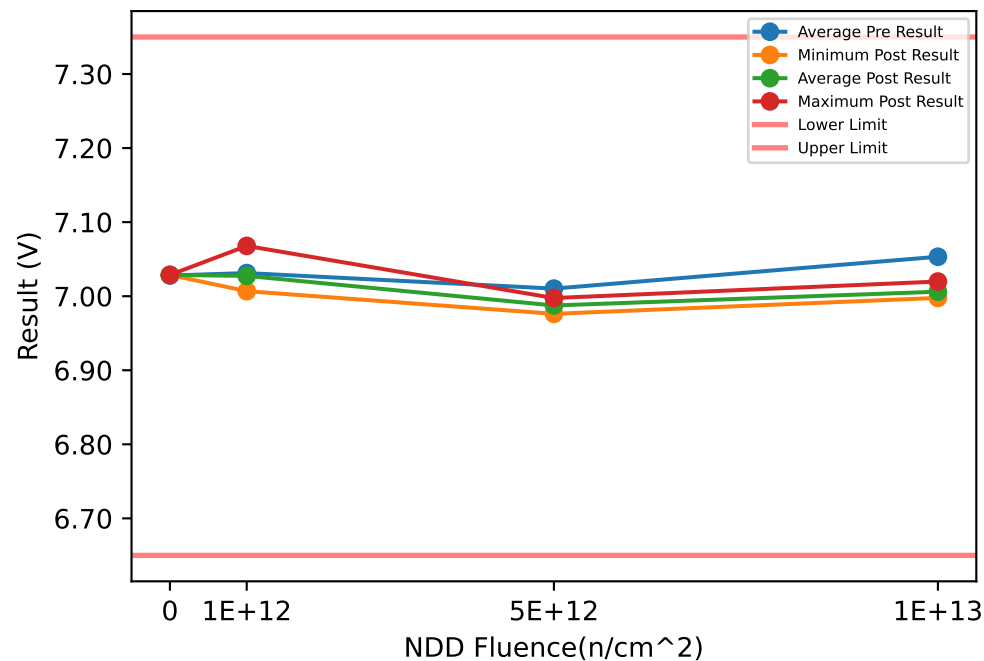


Test Statistics (A)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.5309	2.5309	2.5309		2.5104	2.5104	2.5104		-0.0205	-0.0205	-0.0205	
1e+12	2.5068	2.5388	2.5704	0.031802	2.4993	2.5305	2.5605	0.030618	-0.0099	-0.0083	-0.0075	0.0013856
5e+12	2.538	2.5514	2.5743	0.019904	2.525	2.5417	2.5684	0.023364	-0.013	-0.0097333	-0.0059	0.0035838
1e+13	2.5372	2.5418	2.5495	0.0066876	2.5266	2.5313	2.5384	0.0062554	-0.0111	-0.010533	-0.0099	0.00060277

Device Test: 60.0 V_BP7L(V_BP7L PWM 500kHz VIN_10V)

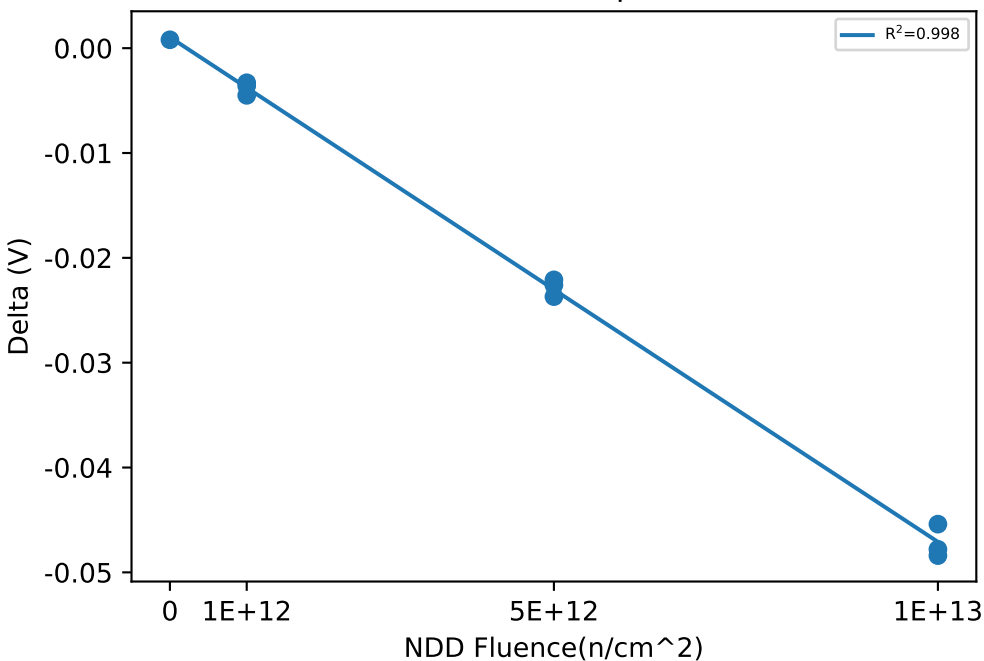
NDD vs Result Stats



Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	7.0101	7.0068	-0.0033
551	1e+12	NDD	7.0112	7.0076	-0.0036
552	1e+12	NDD	7.0724	7.0679	-0.0045
553	5e+12	NDD	7.0196	6.9975	-0.0221
554	5e+12	NDD	7.0124	6.9887	-0.0237
555	5e+12	NDD	6.9988	6.9762	-0.0226
556	1e+13	NDD	7.0431	6.9977	-0.0454
557	1e+13	NDD	7.0676	7.0198	-0.0478
558	1e+13	NDD	7.0491	7.0007	-0.0484
559	0	NDD, Ctrl	7.0279	7.0287	0.0008

NDD vs Post - Pre Exposure Delta

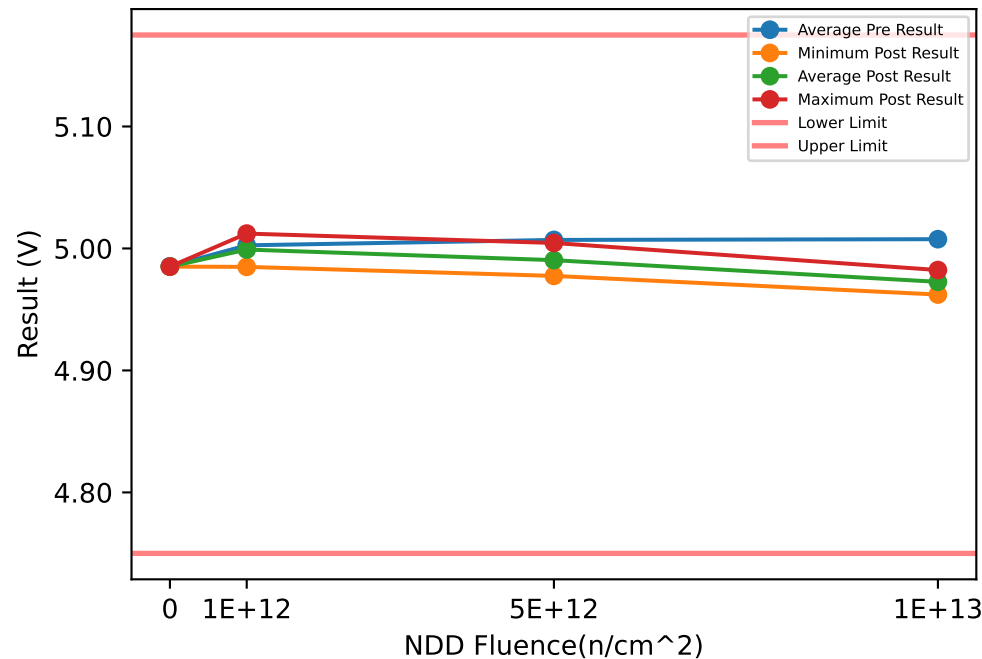


Test Statistics (V)

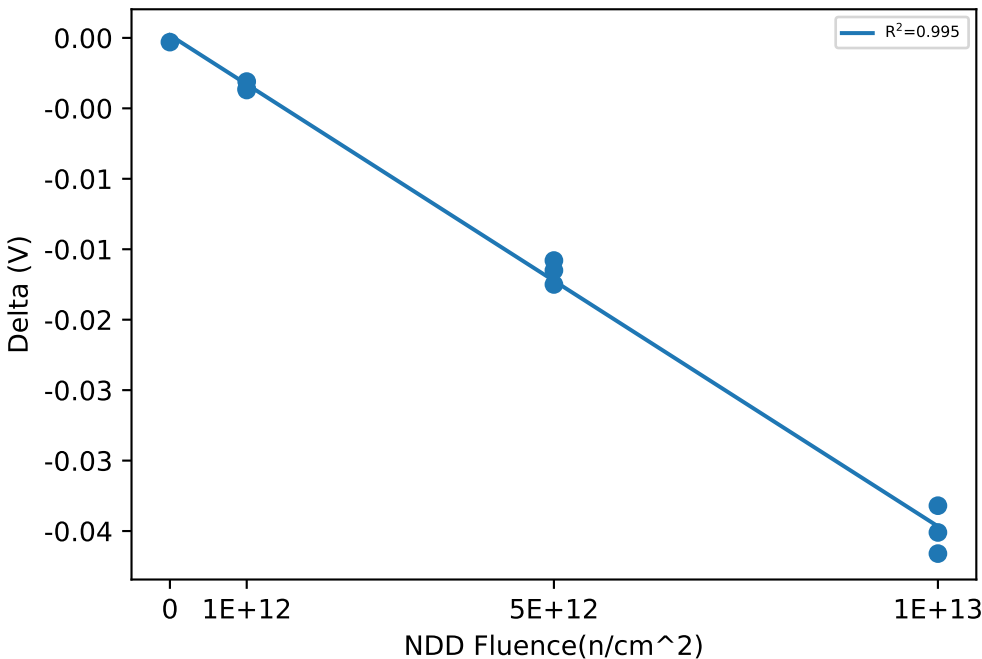
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0279	7.0279	7.0279		7.0287	7.0287	7.0287		0.0008	0.0008	0.0008	
1e+12	7.0101	7.0312	7.0724	0.035656	7.0068	7.0274	7.0679	0.035047	-0.0045	-0.0038	-0.0033	0.0006245
5e+12	6.9988	7.0103	7.0196	0.010563	6.9762	6.9875	6.9975	0.010703	-0.0237	-0.0228	-0.0221	0.00081854
1e+13	7.0431	7.0533	7.0676	0.01277	6.9977	7.0061	7.0198	0.011988	-0.0484	-0.0472	-0.0454	0.0015875

Device Test: 60.1 V_BP5L(V_BP5L PWM 500kHz VIN_10V)

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

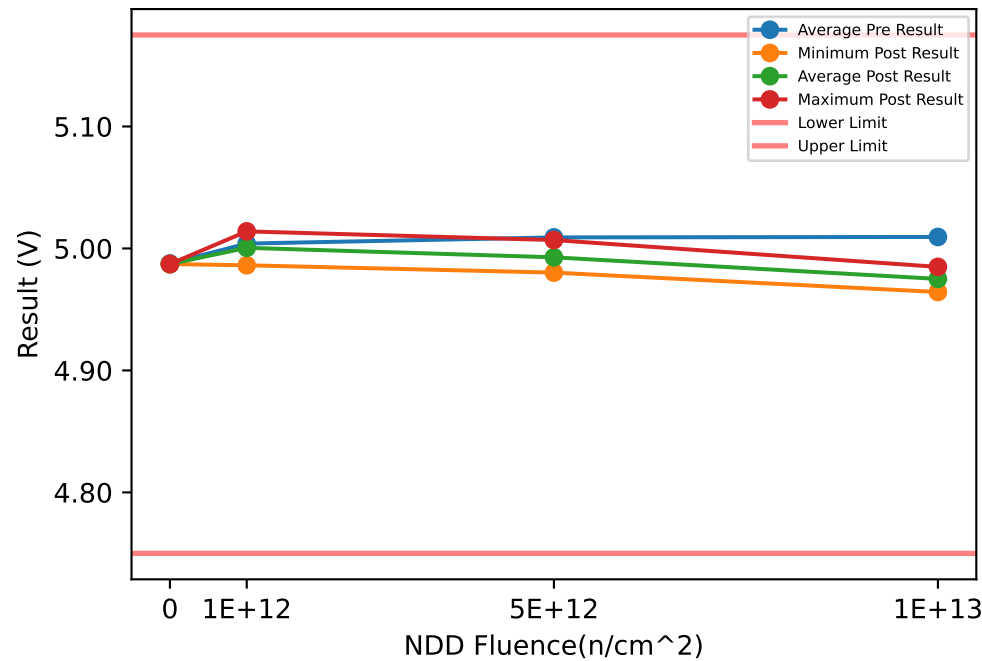
Serial #	Fluence(n/cm ²)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.9885	4.9849	-0.0036
551	1e+12	NDD	5.0039	5.0002	-0.0037
552	1e+12	NDD	5.0153	5.0122	-0.0031
553	5e+12	NDD	5.005	4.9892	-0.0158
554	5e+12	NDD	4.995	4.9775	-0.0175
555	5e+12	NDD	5.021	5.0045	-0.0165
556	1e+13	NDD	4.9973	4.9622	-0.0351
557	1e+13	NDD	5.0155	4.9823	-0.0332
558	1e+13	NDD	5.01	4.9734	-0.0366
559	0	NDD, Ctrl	4.9854	4.9851	-0.0003

Test Statistics (V)

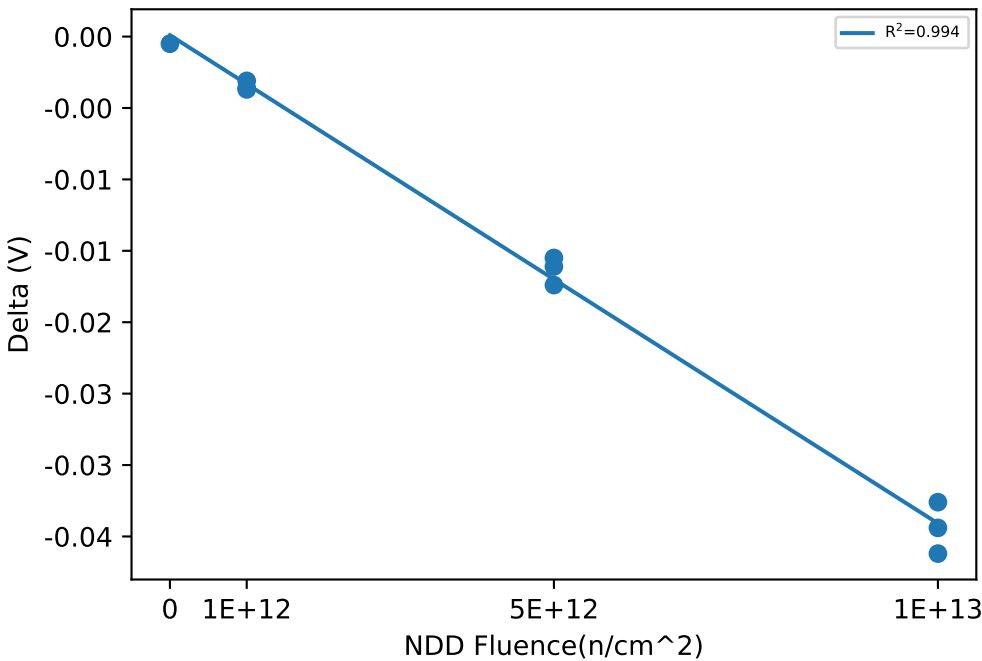
Fluence(n/cm ²)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9854	4.9854	4.9854		4.9851	4.9851	4.9851		-0.0003	-0.0003	-0.0003	
1e+12	4.9885	5.0026	5.0153	0.01345	4.9849	4.9991	5.0122	0.013683	-0.0037	-0.0034667	-0.0031	0.00032146
5e+12	4.995	5.007	5.021	0.013115	4.9775	4.9904	5.0045	0.01354	-0.0175	-0.0166	-0.0158	0.0008544
1e+13	4.9973	5.0076	5.0155	0.0093343	4.9622	4.9726	4.9823	0.010072	-0.0366	-0.034967	-0.0332	0.0017039

Device Test: 60.10 V_BP5L(V_BP5L PWM 5MHz VIN_10V)

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

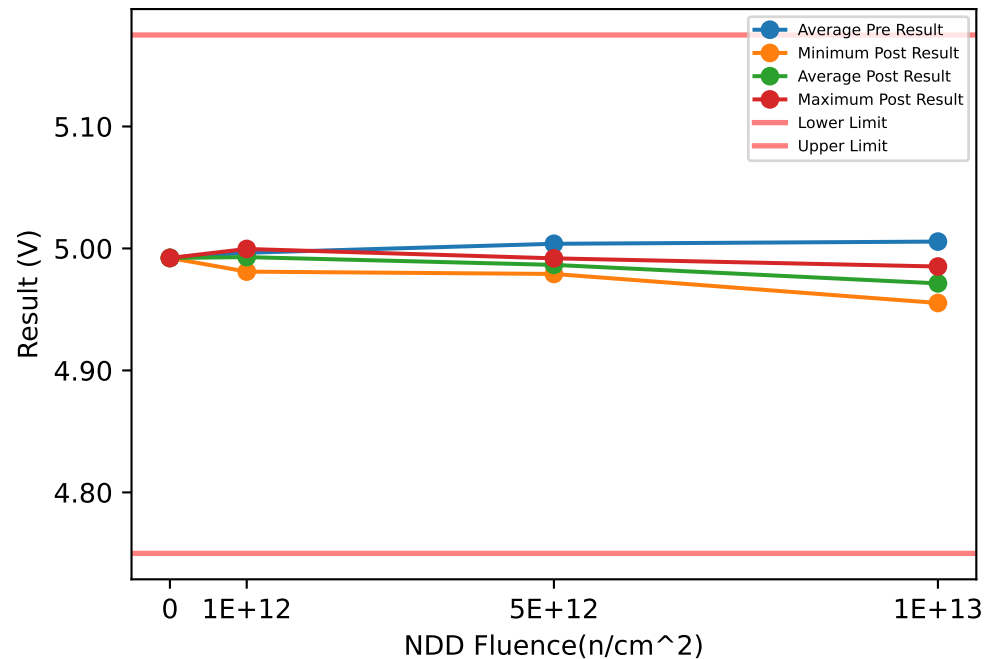
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.9898	4.9862	-0.0036
551	1e+12	NDD	5.0051	5.0014	-0.0037
552	1e+12	NDD	5.0171	5.014	-0.0031
553	5e+12	NDD	5.0066	4.9911	-0.0155
554	5e+12	NDD	4.9976	4.9802	-0.0174
555	5e+12	NDD	5.023	5.0069	-0.0161
556	1e+13	NDD	4.9987	4.9643	-0.0344
557	1e+13	NDD	5.0175	4.9849	-0.0326
558	1e+13	NDD	5.0121	4.9759	-0.0362
559	0	NDD, Ctrl	4.9877	4.9872	-0.0005

Test Statistics (V)

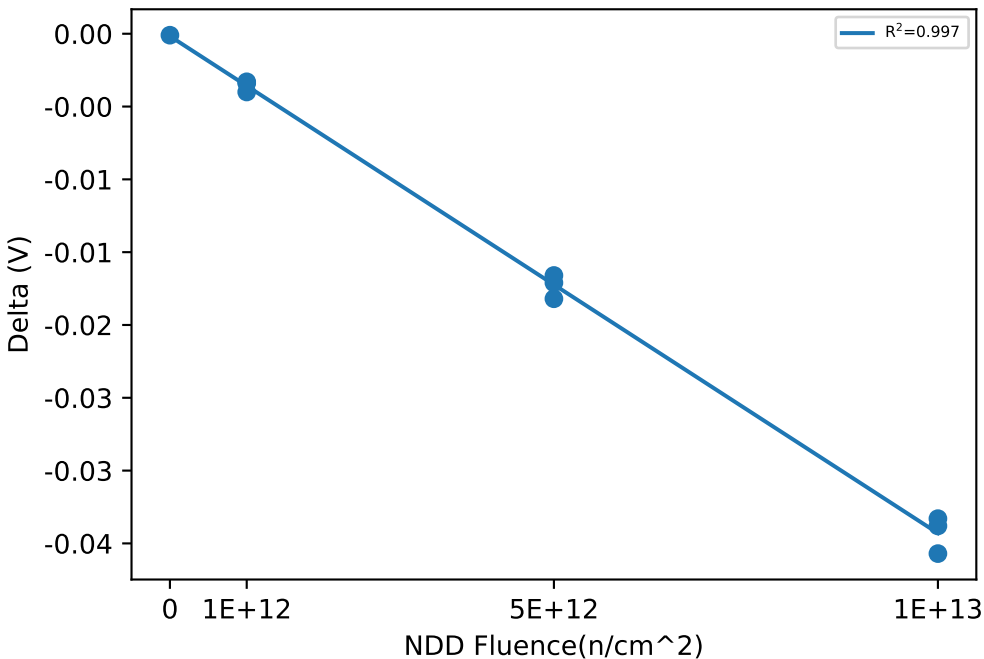
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9877	4.9877	4.9877		4.9872	4.9872	4.9872		-0.0005	-0.0005	-0.0005	
1e+12	4.9898	5.004	5.0171	0.013683	4.9862	5.0005	5.014	0.01392	-0.0037	-0.0034667	-0.0031	0.00032146
5e+12	4.9976	5.0091	5.023	0.012878	4.9802	4.9927	5.0069	0.013425	-0.0174	-0.016333	-0.0155	0.00097125
1e+13	4.9987	5.0094	5.0175	0.0096795	4.9643	4.975	4.9849	0.010327	-0.0362	-0.0344	-0.0326	0.0018

Device Test: 60.11 V_BP5H(V_BP5H PWM 5MHz VIN_10V)

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

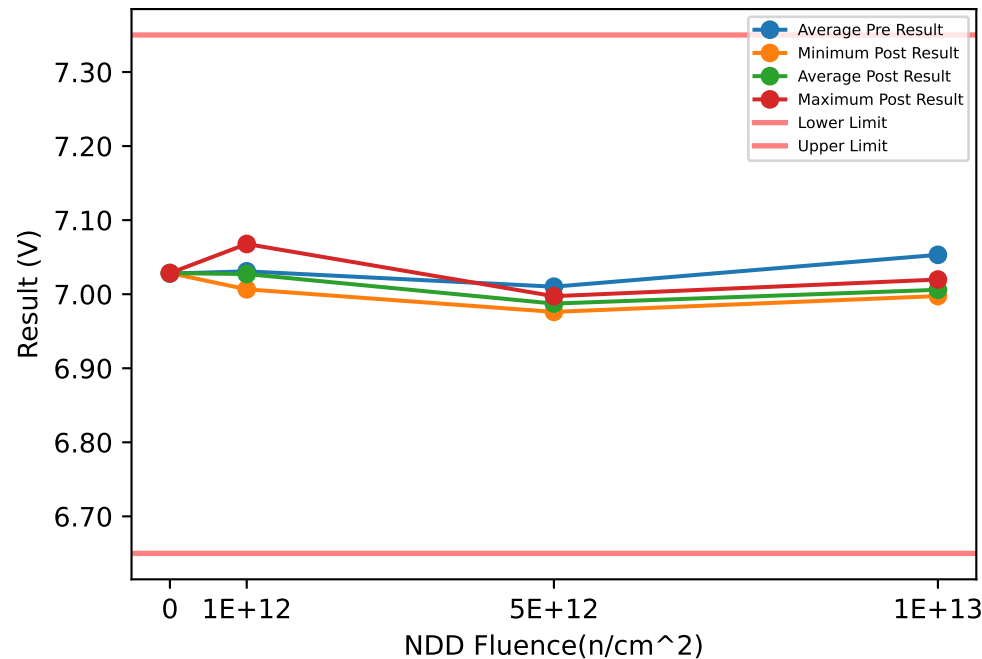
Serial #	Fluence(n/cm ²)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.985	4.981	-0.004
551	1e+12	NDD	5.0015	4.9981	-0.0034
552	1e+12	NDD	5.0029	4.9996	-0.0033
553	5e+12	NDD	4.9973	4.9791	-0.0182
554	5e+12	NDD	5.009	4.9919	-0.0171
555	5e+12	NDD	5.0052	4.9886	-0.0166
556	1e+13	NDD	4.9886	4.9553	-0.0333
557	1e+13	NDD	5.0209	4.9852	-0.0357
558	1e+13	NDD	5.0074	4.9736	-0.0338
559	0	NDD, Ctrl	4.9923	4.9922	-0.0001

Test Statistics (V)

Fluence(n/cm ²)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9923	4.9923	4.9923		4.9922	4.9922	4.9922		-0.0001	-0.0001	-0.0001	
1e+12	4.985	4.9965	5.0029	0.0099551	4.981	4.9929	4.9996	0.010333	-0.004	-0.0035667	-0.0033	0.00037859
5e+12	4.9973	5.0038	5.009	0.0059685	4.9791	4.9865	4.9919	0.0066455	-0.0182	-0.0173	-0.0166	0.00081854
1e+13	4.9886	5.0056	5.0209	0.016222	4.9553	4.9714	4.9852	0.015075	-0.0357	-0.034267	-0.0333	0.0012662

Device Test: 60.12 V_BP7L(V_BP7L IIM 500kHz VIN_10V)

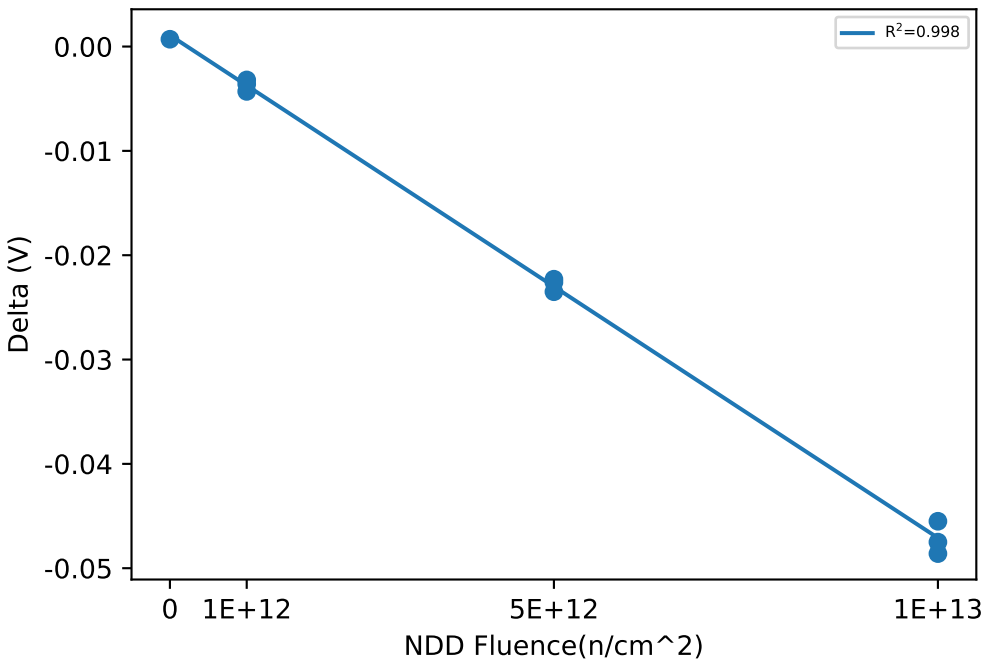
NDD vs Result Stats



Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	7.0098	7.0066	-0.0032
551	1e+12	NDD	7.0108	7.0072	-0.0036
552	1e+12	NDD	7.0721	7.0678	-0.0043
553	5e+12	NDD	7.0196	6.9973	-0.0223
554	5e+12	NDD	7.0121	6.9886	-0.0235
555	5e+12	NDD	6.9987	6.9761	-0.0226
556	1e+13	NDD	7.043	6.9975	-0.0455
557	1e+13	NDD	7.0673	7.0198	-0.0475
558	1e+13	NDD	7.0491	7.0005	-0.0486
559	0	NDD, Ctrl	7.0278	7.0285	0.0007

NDD vs Post - Pre Exposure Delta

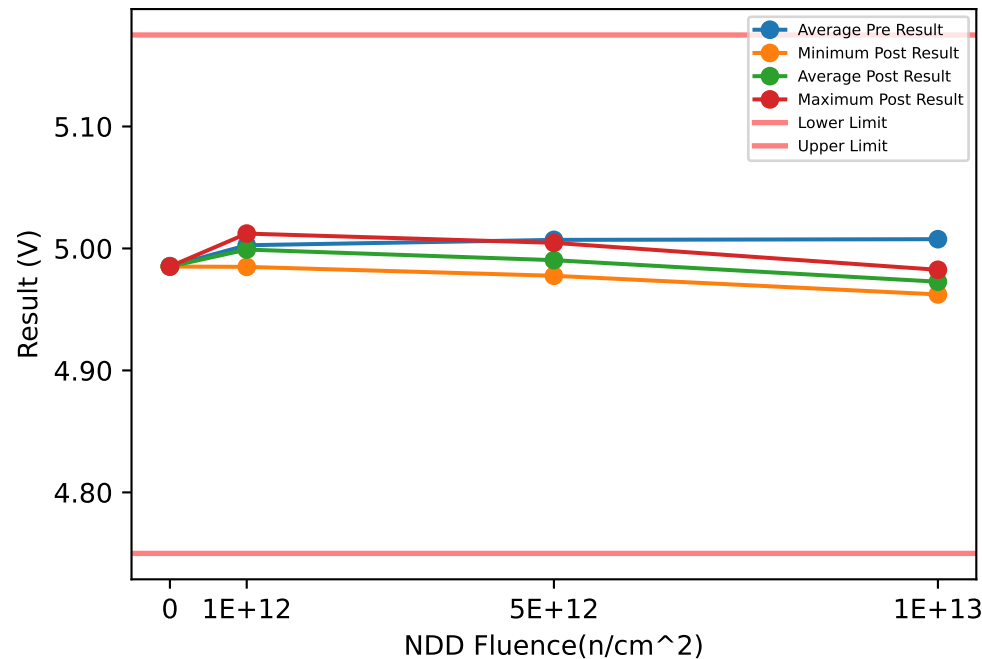


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0278	7.0278	7.0278		7.0285	7.0285	7.0285		0.0007	0.0007	0.0007	
1e+12	7.0098	7.0309	7.0721	0.035684	7.0066	7.0272	7.0678	0.035162	-0.0043	-0.0037	-0.0032	0.00055678
5e+12	6.9987	7.0101	7.0196	0.010588	6.9761	6.9873	6.9973	0.010657	-0.0235	-0.0228	-0.0223	0.0006245
1e+13	7.043	7.0531	7.0673	0.012642	6.9975	7.0059	7.0198	0.012102	-0.0486	-0.0472	-0.0455	0.0015716

Device Test: 60.13 V_BP5L(V_BP5L IIM 500kHz VIN_10V)

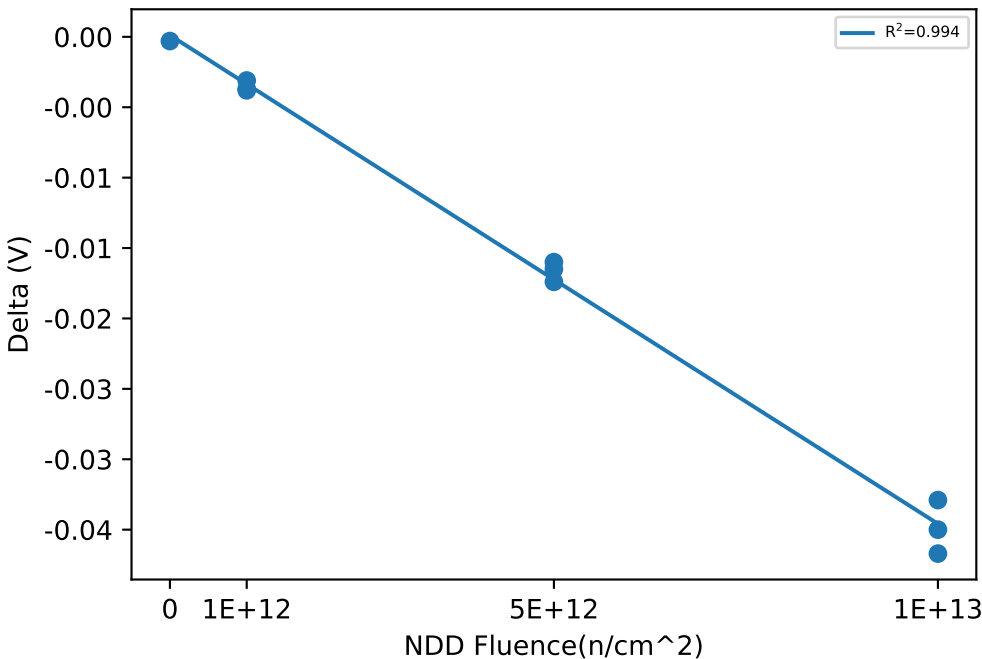
NDD vs Result Stats



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

Serial #	Fluence(n/cm ²)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.9886	4.9849	-0.0037
551	1e+12	NDD	5.004	5.0002	-0.0038
552	1e+12	NDD	5.0153	5.0122	-0.0031
553	5e+12	NDD	5.005	4.989	-0.016
554	5e+12	NDD	4.995	4.9776	-0.0174
555	5e+12	NDD	5.0211	5.0046	-0.0165
556	1e+13	NDD	4.9973	4.9623	-0.035
557	1e+13	NDD	5.0154	4.9825	-0.0329
558	1e+13	NDD	5.0101	4.9734	-0.0367
559	0	NDD, Ctrl	4.9855	4.9852	-0.0003

NDD vs Post - Pre Exposure Delta

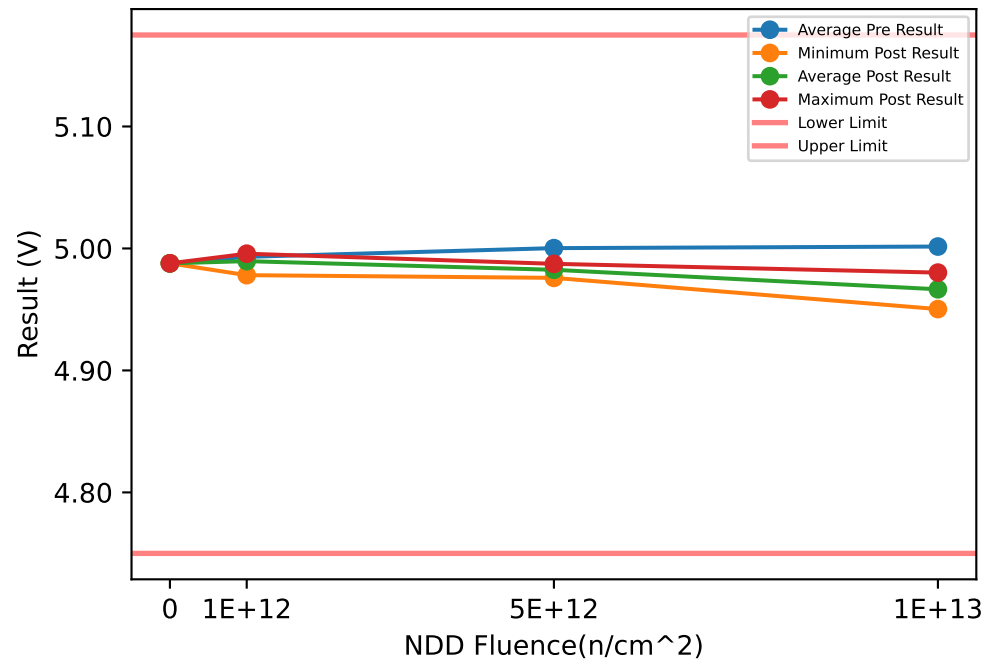


Test Statistics (V)

Fluence(n/cm ²)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9855	4.9855	4.9855		4.9852	4.9852	4.9852		-0.0003	-0.0003	-0.0003	
1e+12	4.9886	5.0026	5.0153	0.013402	4.9849	4.9991	5.0122	0.013683	-0.0038	-0.0035333	-0.0031	0.00037859
5e+12	4.995	5.007	5.0211	0.013168	4.9776	4.9904	5.0046	0.013554	-0.0174	-0.016633	-0.016	0.00070946
1e+13	4.9973	5.0076	5.0154	0.0093054	4.9623	4.9727	4.9825	0.010116	-0.0367	-0.034867	-0.0329	0.0019035

Device Test: 60.14 V_BP5H(V_BP5H IIM 500kHz VIN_10V)

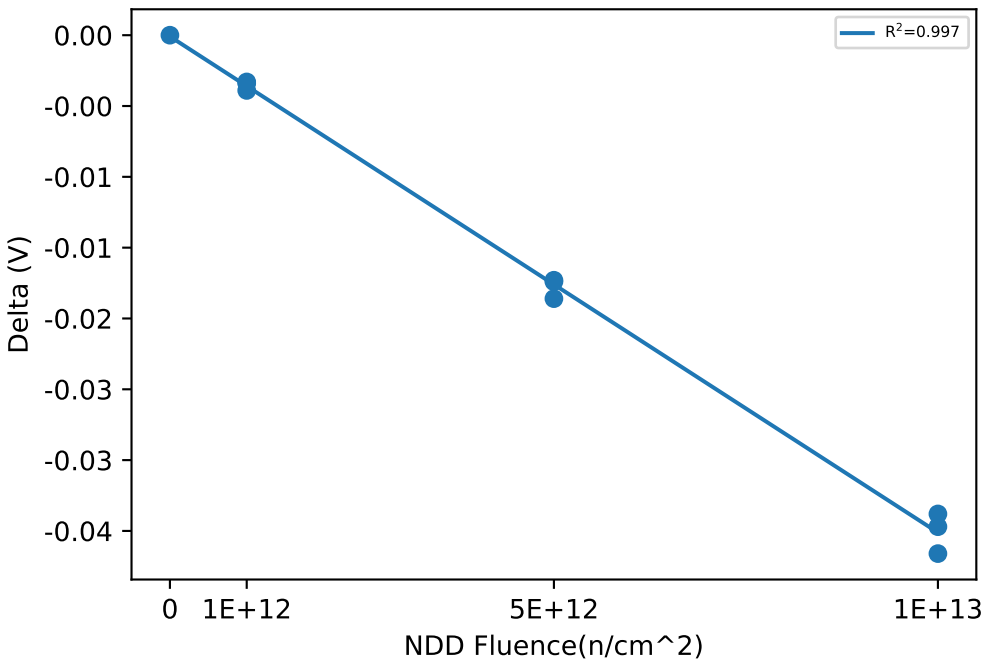
NDD vs Result Stats



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.982	4.9781	-0.0039
551	1e+12	NDD	4.9983	4.995	-0.0033
552	1e+12	NDD	4.9991	4.9957	-0.0034
553	5e+12	NDD	4.9945	4.9759	-0.0186
554	5e+12	NDD	5.0048	4.9874	-0.0174
555	5e+12	NDD	5.0015	4.9842	-0.0173
556	1e+13	NDD	4.9841	4.9503	-0.0338
557	1e+13	NDD	5.0168	4.9802	-0.0366
558	1e+13	NDD	5.0038	4.9691	-0.0347
559	0	NDD, Ctrl	4.9878	4.9878	0

NDD vs Post - Pre Exposure Delta

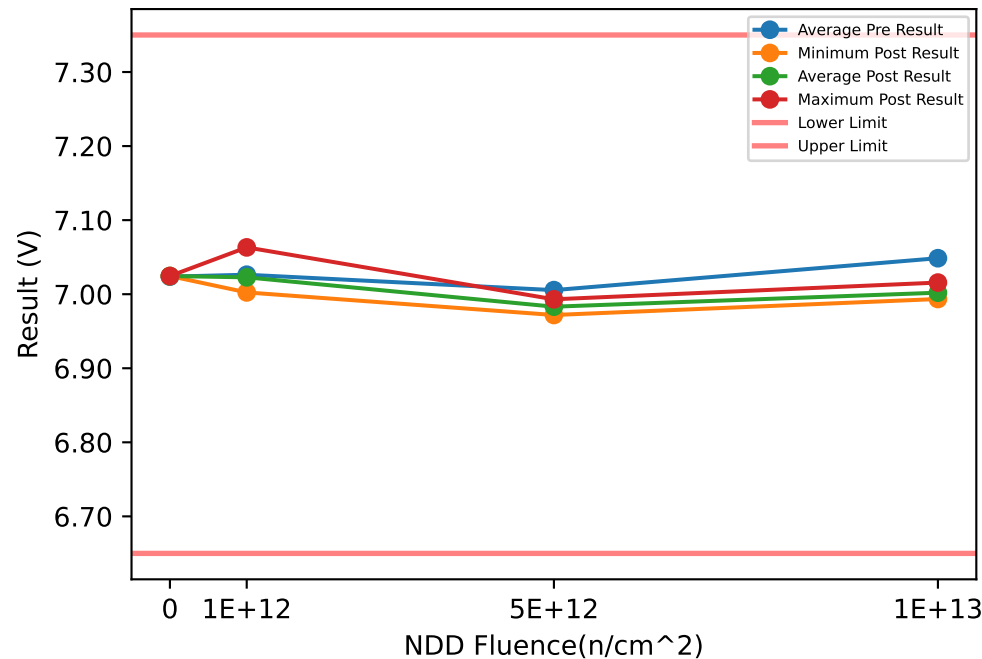


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9878	4.9878	4.9878		4.9878	4.9878	4.9878		0	0	0	
1e+12	4.982	4.9931	4.9991	0.00965	4.9781	4.9896	4.9957	0.0099654	-0.0039	-0.0035333	-0.0033	0.00032146
5e+12	4.9945	5.0003	5.0048	0.0052596	4.9759	4.9825	4.9874	0.0059355	-0.0186	-0.017767	-0.0173	0.00072342
1e+13	4.9841	5.0016	5.0168	0.016464	4.9503	4.9665	4.9802	0.015114	-0.0366	-0.035033	-0.0338	0.0014295

Device Test: 60.15 V_BP7L(V_BP7L IIM 1MHz VIN_10V)

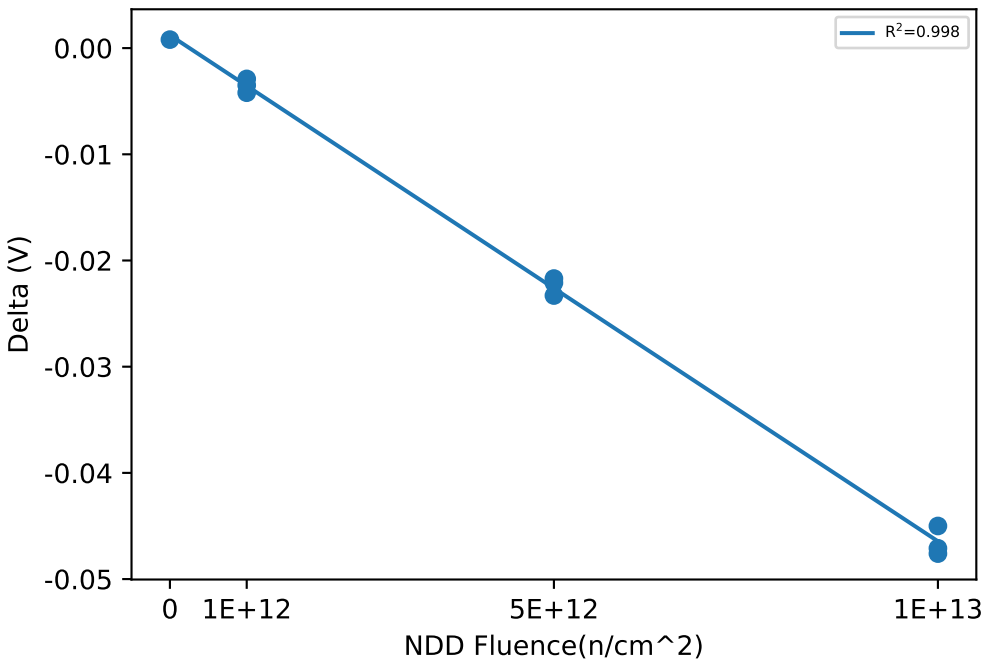
NDD vs Result Stats



Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	7.0053	7.0024	-0.0029
551	1e+12	NDD	7.0062	7.0027	-0.0035
552	1e+12	NDD	7.0674	7.0632	-0.0042
553	5e+12	NDD	7.0148	6.9931	-0.0217
554	5e+12	NDD	7.0077	6.9844	-0.0233
555	5e+12	NDD	6.994	6.9719	-0.0221
556	1e+13	NDD	7.0385	6.9935	-0.045
557	1e+13	NDD	7.0628	7.0157	-0.0471
558	1e+13	NDD	7.0445	6.9969	-0.0476
559	0	NDD, Ctrl	7.0237	7.0245	0.0008

NDD vs Post - Pre Exposure Delta

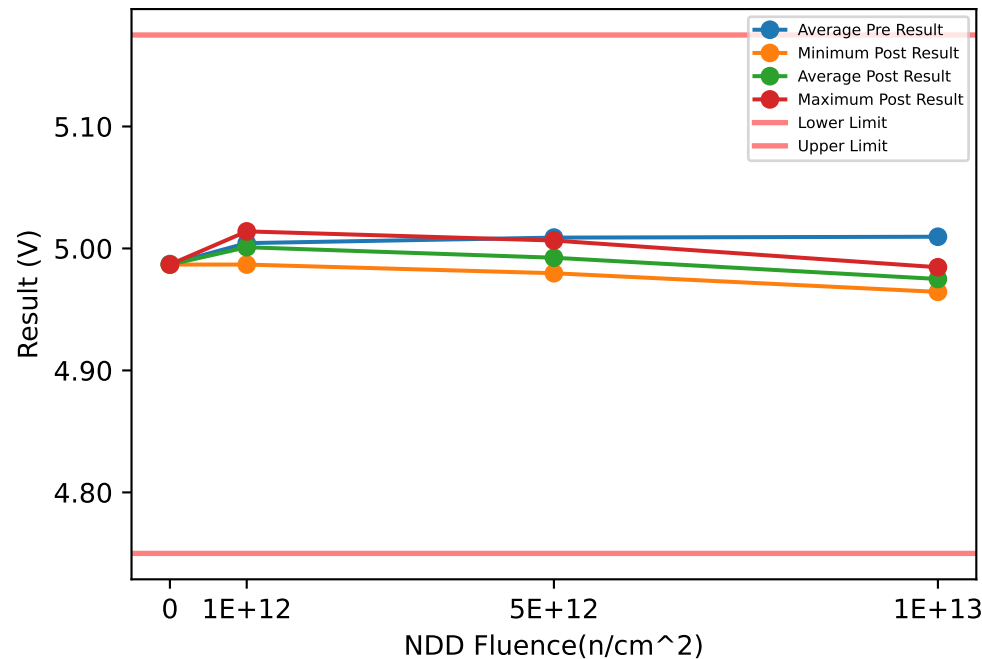


Test Statistics (V)

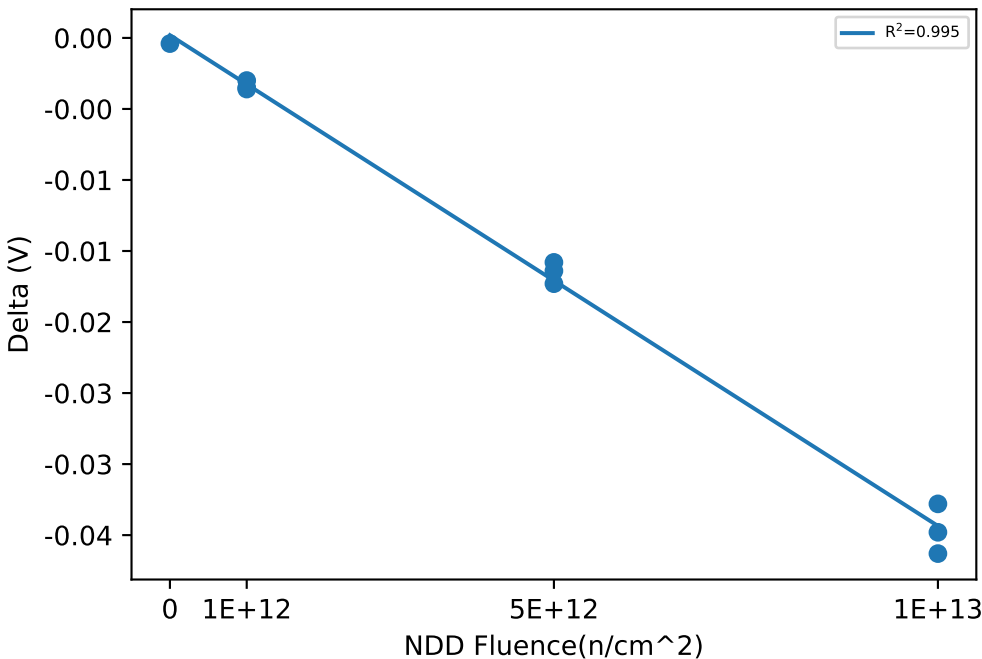
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0237	7.0237	7.0237		7.0245	7.0245	7.0245		0.0008	0.0008	0.0008	
1e+12	7.0053	7.0263	7.0674	0.035596	7.0024	7.0228	7.0632	0.035017	-0.0042	-0.0035333	-0.0029	0.00065064
5e+12	6.994	7.0055	7.0148	0.010573	6.9719	6.9831	6.9931	0.010657	-0.0233	-0.022367	-0.0217	0.00083267
1e+13	7.0385	7.0486	7.0628	0.012658	6.9935	7.002	7.0157	0.011957	-0.0476	-0.046567	-0.045	0.0013796

Device Test: 60.16 V_BP5L(V_BP5L IIM 1MHz VIN_10V)

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

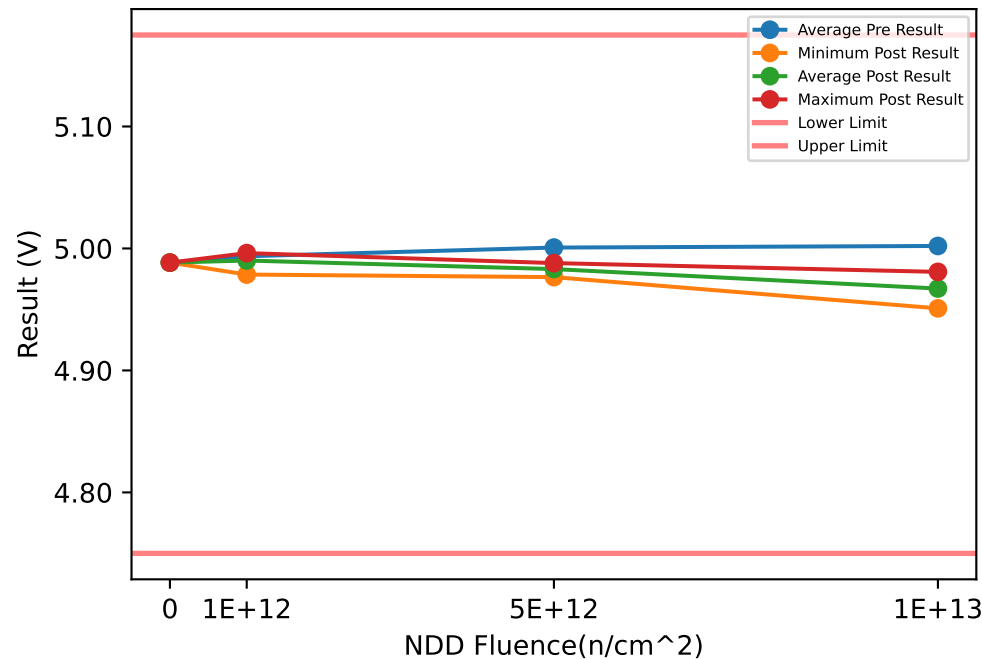
Serial #	Fluence(n/cm ²)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.9903	4.9868	-0.0035
551	1e+12	NDD	5.0058	5.0022	-0.0036
552	1e+12	NDD	5.017	5.014	-0.003
553	5e+12	NDD	5.0068	4.991	-0.0158
554	5e+12	NDD	4.997	4.9797	-0.0173
555	5e+12	NDD	5.0229	5.0065	-0.0164
556	1e+13	NDD	4.9992	4.9644	-0.0348
557	1e+13	NDD	5.0174	4.9846	-0.0328
558	1e+13	NDD	5.0122	4.9759	-0.0363
559	0	NDD, Ctrl	4.9872	4.9868	-0.0004

Test Statistics (V)

Fluence(n/cm ²)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9872	4.9872	4.9872		4.9868	4.9868	4.9868		-0.0004	-0.0004	-0.0004	
1e+12	4.9903	5.0044	5.017	0.013408	4.9868	5.001	5.014	0.01364	-0.0036	-0.0033667	-0.003	0.00032146
5e+12	4.997	5.0089	5.0229	0.013077	4.9797	4.9924	5.0065	0.013455	-0.0173	-0.0165	-0.0158	0.00075498
1e+13	4.9992	5.0096	5.0174	0.0093744	4.9644	4.975	4.9846	0.010132	-0.0363	-0.034633	-0.0328	0.0017559

Device Test: 60.17 V_BP5H(V_BP5H IIM 1MHz VIN_10V)

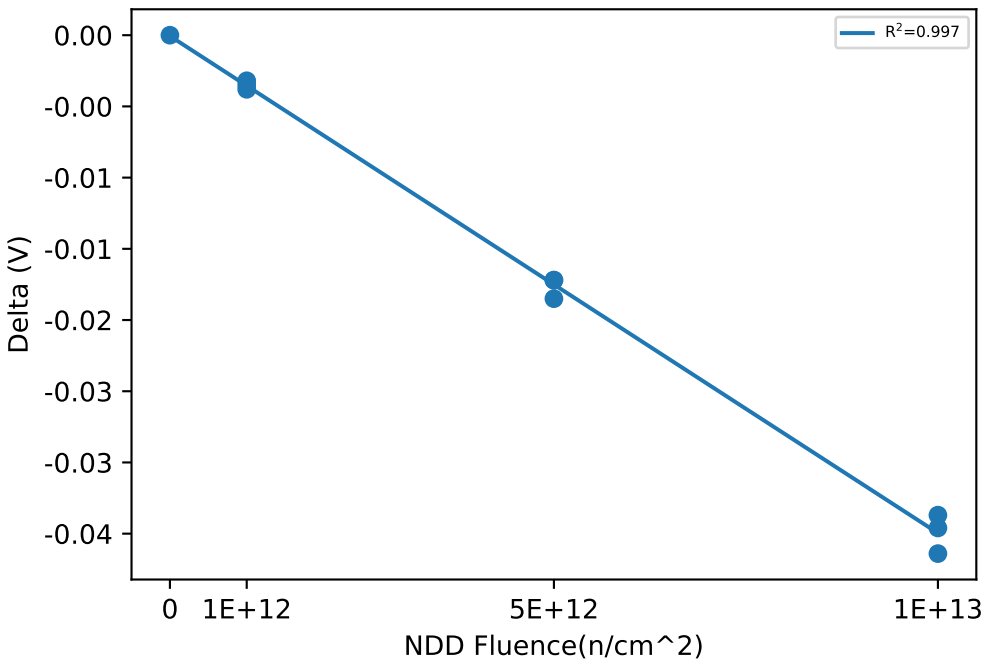
NDD vs Result Stats



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

Serial #	Fluence(n/cm ²)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.9824	4.9786	-0.0038
551	1e+12	NDD	4.9987	4.9955	-0.0032
552	1e+12	NDD	4.9997	4.9962	-0.0035
553	5e+12	NDD	4.995	4.9765	-0.0185
554	5e+12	NDD	5.0052	4.988	-0.0172
555	5e+12	NDD	5.002	4.9848	-0.0172
556	1e+13	NDD	4.9846	4.9509	-0.0337
557	1e+13	NDD	5.0172	4.9808	-0.0364
558	1e+13	NDD	5.0043	4.9697	-0.0346
559	0	NDD, Ctrl	4.9884	4.9884	0

NDD vs Post - Pre Exposure Delta

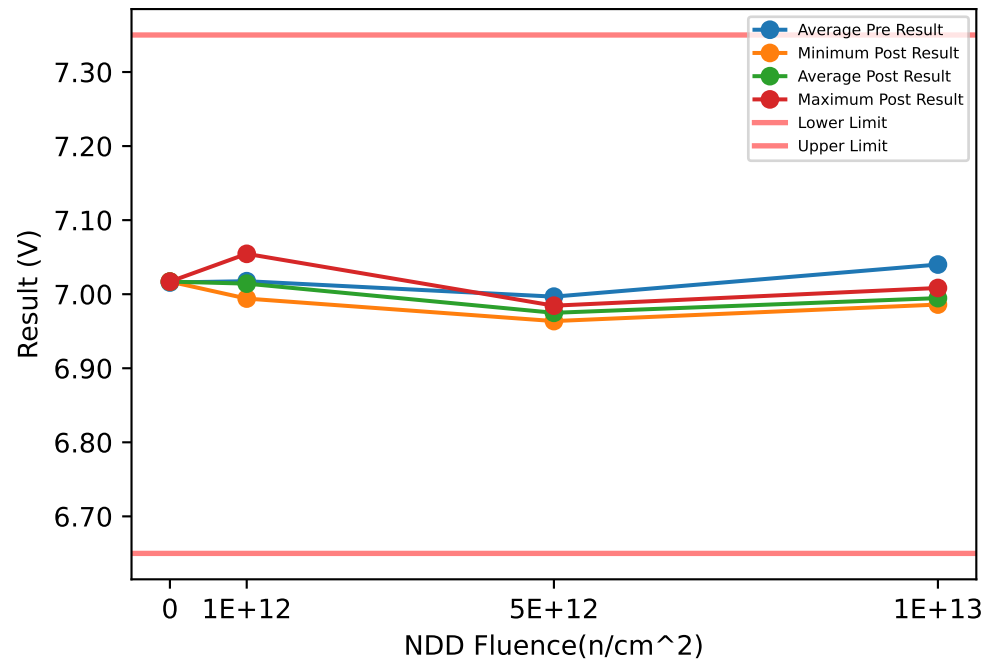


Test Statistics (V)

Fluence(n/cm ²)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9884	4.9884	4.9884		4.9884	4.9884	4.9884		0	0	0	
1e+12	4.9824	4.9936	4.9997	0.0097124	4.9786	4.9901	4.9962	0.0099654	-0.0038	-0.0035	-0.0032	0.0003
5e+12	4.995	5.0007	5.0052	0.0052166	4.9765	4.9831	4.988	0.0059355	-0.0185	-0.017633	-0.0172	0.00075056
1e+13	4.9846	5.002	5.0172	0.016418	4.9509	4.9671	4.9808	0.015114	-0.0364	-0.0349	-0.0337	0.0013748

Device Test: 60.18 V_BP7L(V_BP7L IIM 2MHz VIN_10V)

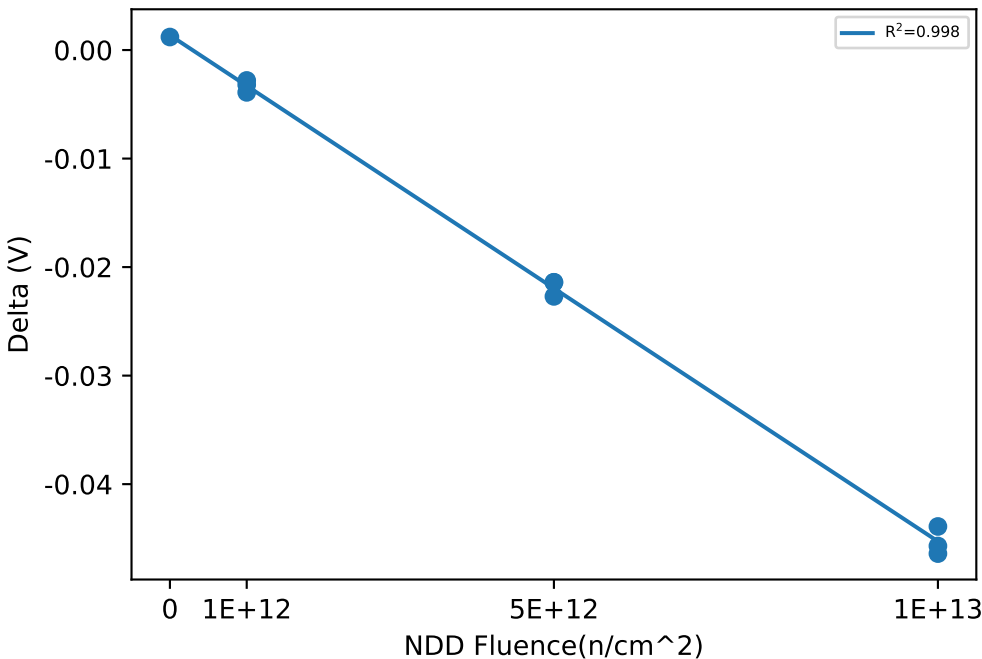
NDD vs Result Stats



Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	6.997	6.9942	-0.0028
551	1e+12	NDD	6.9973	6.9941	-0.0032
552	1e+12	NDD	7.0584	7.0545	-0.0039
553	5e+12	NDD	7.0059	6.9845	-0.0214
554	5e+12	NDD	6.9991	6.9764	-0.0227
555	5e+12	NDD	6.9851	6.9637	-0.0214
556	1e+13	NDD	7.0299	6.986	-0.0439
557	1e+13	NDD	7.0541	7.0084	-0.0457
558	1e+13	NDD	7.0361	6.9897	-0.0464
559	0	NDD, Ctrl	7.0158	7.017	0.0012

NDD vs Post - Pre Exposure Delta

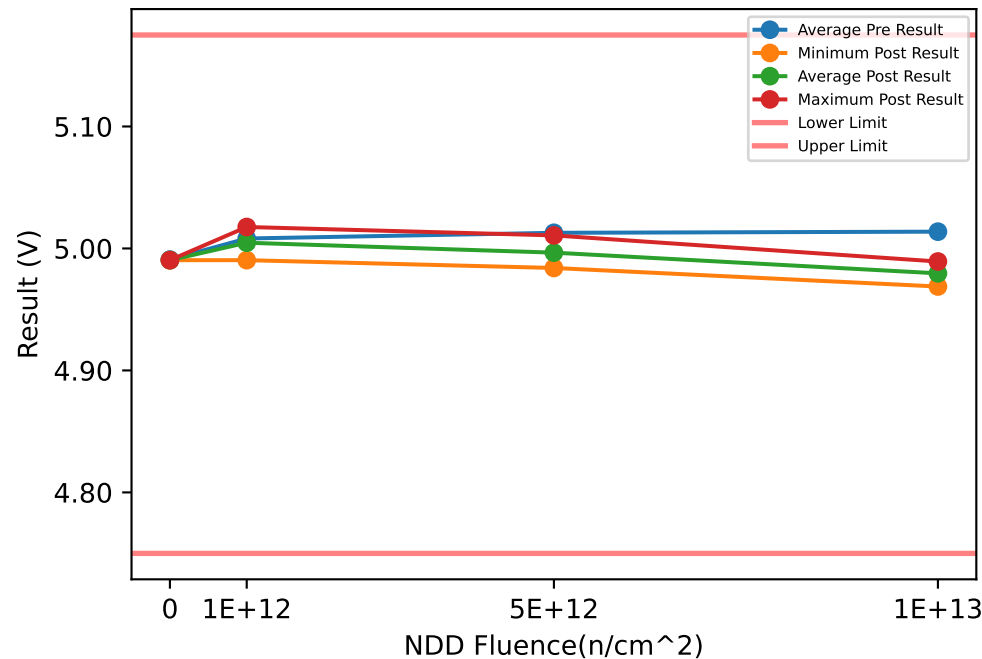


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0158	7.0158	7.0158		7.017	7.017	7.017		0.0012	0.0012	0.0012	
1e+12	6.997	7.0176	7.0584	0.035363	6.9941	7.0143	7.0545	0.034843	-0.0039	-0.0033	-0.0028	0.00055678
5e+12	6.9851	6.9967	7.0059	0.010606	6.9637	6.9749	6.9845	0.010484	-0.0227	-0.021833	-0.0214	0.00075056
1e+13	7.0299	7.04	7.0541	0.01257	6.986	6.9947	7.0084	0.012008	-0.0464	-0.045333	-0.0439	0.0012897

Device Test: 60.19 V_BP5L(V_BP5L IIM 2MHz VIN_10V)

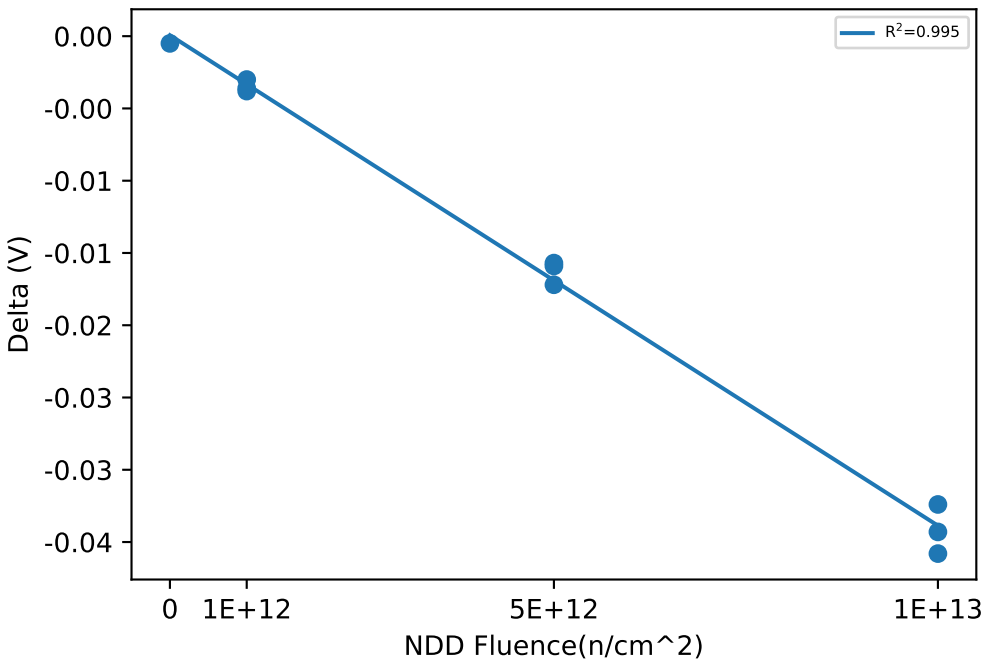
NDD vs Result Stats



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.994	4.9904	-0.0036
551	1e+12	NDD	5.0099	5.0061	-0.0038
552	1e+12	NDD	5.0206	5.0176	-0.003
553	5e+12	NDD	5.0107	4.995	-0.0157
554	5e+12	NDD	5.0012	4.984	-0.0172
555	5e+12	NDD	5.0266	5.0107	-0.0159
556	1e+13	NDD	5.0031	4.9688	-0.0343
557	1e+13	NDD	5.0217	4.9893	-0.0324
558	1e+13	NDD	5.0165	4.9807	-0.0358
559	0	NDD, Ctrl	4.9909	4.9904	-0.0005

NDD vs Post - Pre Exposure Delta

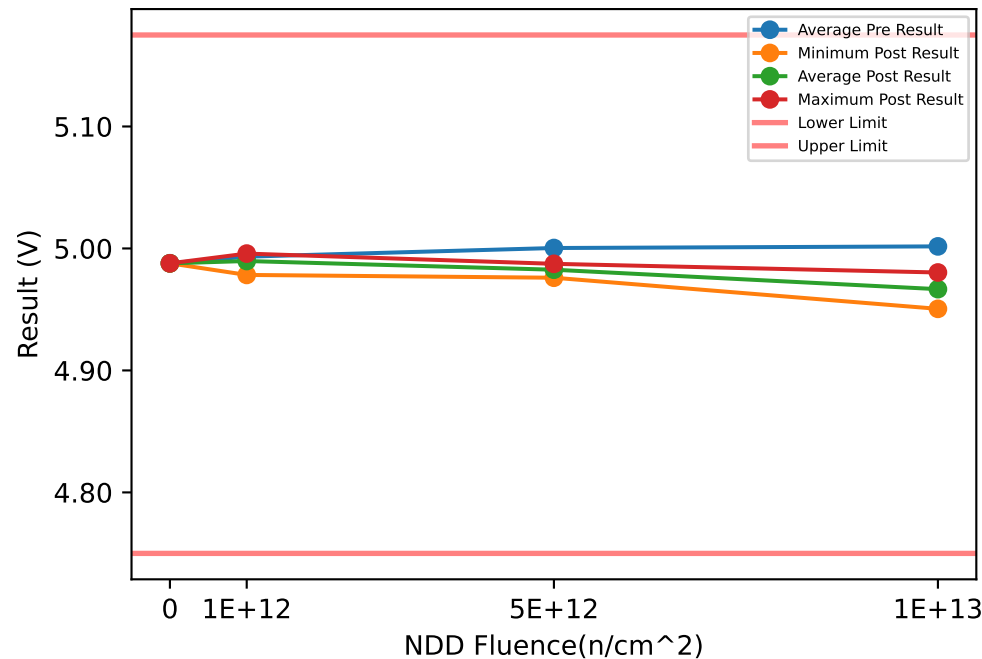


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9909	4.9909	4.9909		4.9904	4.9904	4.9904		-0.0005	-0.0005	-0.0005	
1e+12	4.994	5.0082	5.0206	0.013384	4.9904	5.0047	5.0176	0.013654	-0.0038	-0.0034667	-0.003	0.00041633
5e+12	5.0012	5.0128	5.0266	0.012834	4.984	4.9966	5.0107	0.013419	-0.0172	-0.016267	-0.0157	0.00081445
1e+13	5.0031	5.0138	5.0217	0.0095965	4.9688	4.9796	4.9893	0.010294	-0.0358	-0.034167	-0.0324	0.0017039

Device Test: 60.2 V_BP5H(V_BP5H PWM 500kHz VIN_10V)

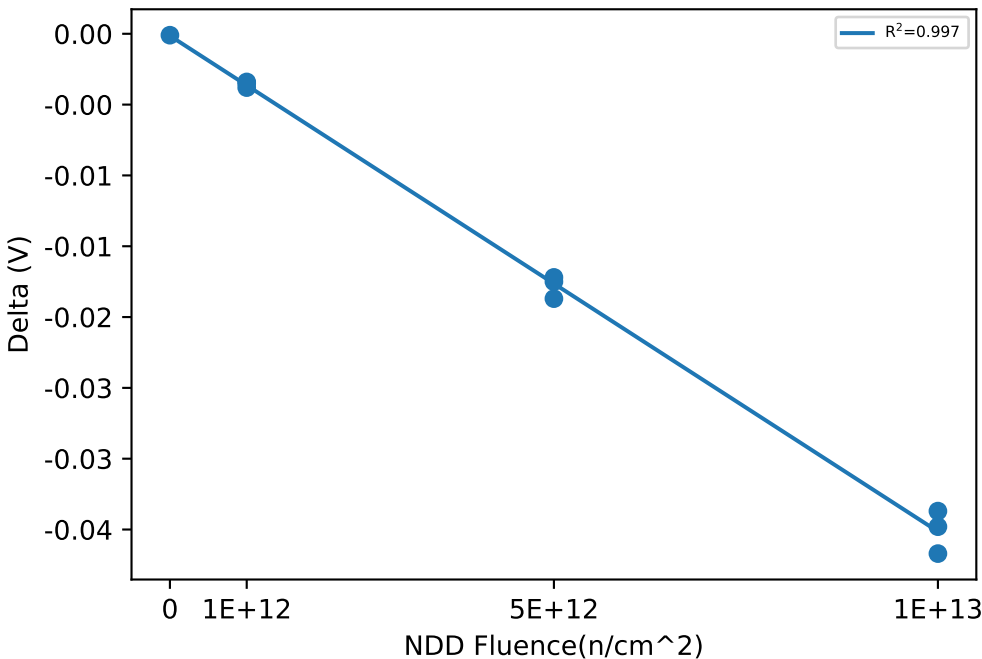
NDD vs Result Stats



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

Serial #	Fluence(n/cm ²)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.9821	4.9783	-0.0038
551	1e+12	NDD	4.9985	4.995	-0.0035
552	1e+12	NDD	4.9992	4.9958	-0.0034
553	5e+12	NDD	4.9947	4.976	-0.0187
554	5e+12	NDD	5.0049	4.9874	-0.0175
555	5e+12	NDD	5.0015	4.9843	-0.0172
556	1e+13	NDD	4.9842	4.9505	-0.0337
557	1e+13	NDD	5.017	4.9803	-0.0367
558	1e+13	NDD	5.0039	4.9691	-0.0348
559	0	NDD, Ctrl	4.9879	4.9878	-0.0001

NDD vs Post - Pre Exposure Delta

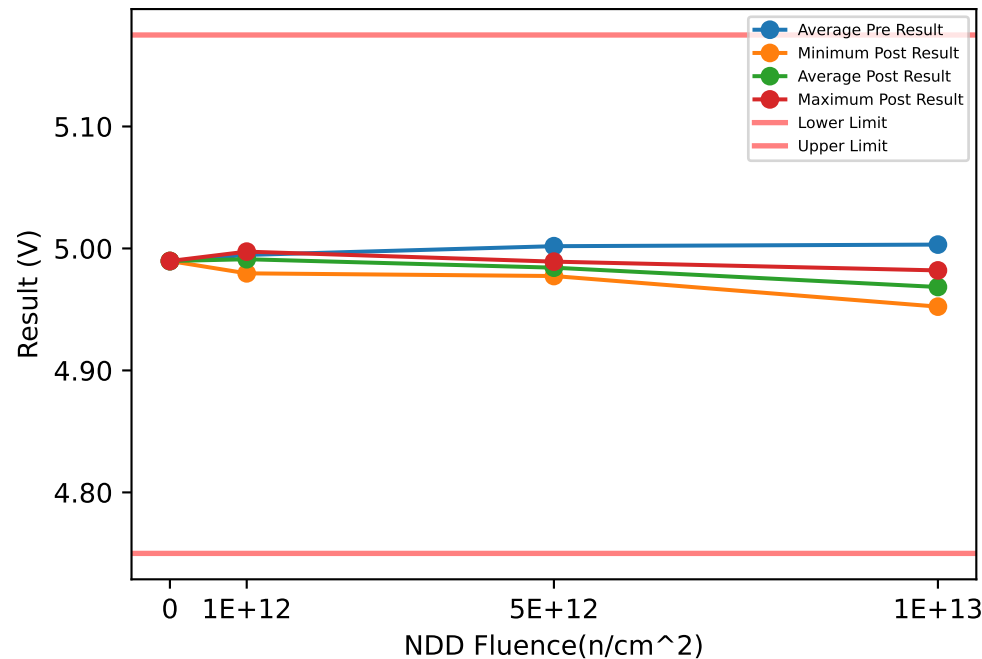


Test Statistics (V)

Fluence(n/cm ²)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9879	4.9879	4.9879		4.9878	4.9878	4.9878		-0.0001	-0.0001	-0.0001	
1e+12	4.9821	4.9933	4.9992	0.0096769	4.9783	4.9897	4.9958	0.0098808	-0.0038	-0.0035667	-0.0034	0.00020817
5e+12	4.9947	5.0004	5.0049	0.0051936	4.976	4.9826	4.9874	0.0058943	-0.0187	-0.0178	-0.0172	0.00079373
1e+13	4.9842	5.0017	5.017	0.01651	4.9505	4.9666	4.9803	0.015052	-0.0367	-0.035067	-0.0337	0.0015177

Device Test: 60.20 V_BP5H(V_BP5H IIM 2MHz VIN_10V)

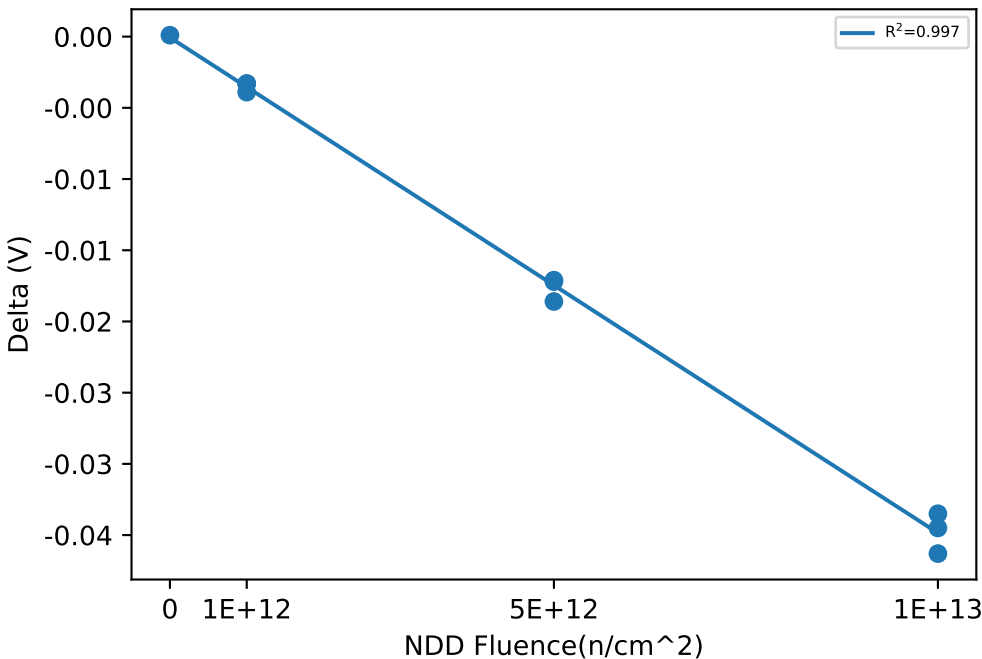
NDD vs Result Stats



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

Serial #	Fluence(n/cm ²)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.9835	4.9796	-0.0039
551	1e+12	NDD	4.9998	4.9965	-0.0033
552	1e+12	NDD	5.0007	4.9974	-0.0033
553	5e+12	NDD	4.996	4.9774	-0.0186
554	5e+12	NDD	5.0064	4.9892	-0.0172
555	5e+12	NDD	5.0032	4.9861	-0.0171
556	1e+13	NDD	4.9858	4.9523	-0.0335
557	1e+13	NDD	5.0183	4.982	-0.0363
558	1e+13	NDD	5.0054	4.9709	-0.0345
559	0	NDD, Ctrl	4.9896	4.9897	0.0001

NDD vs Post - Pre Exposure Delta

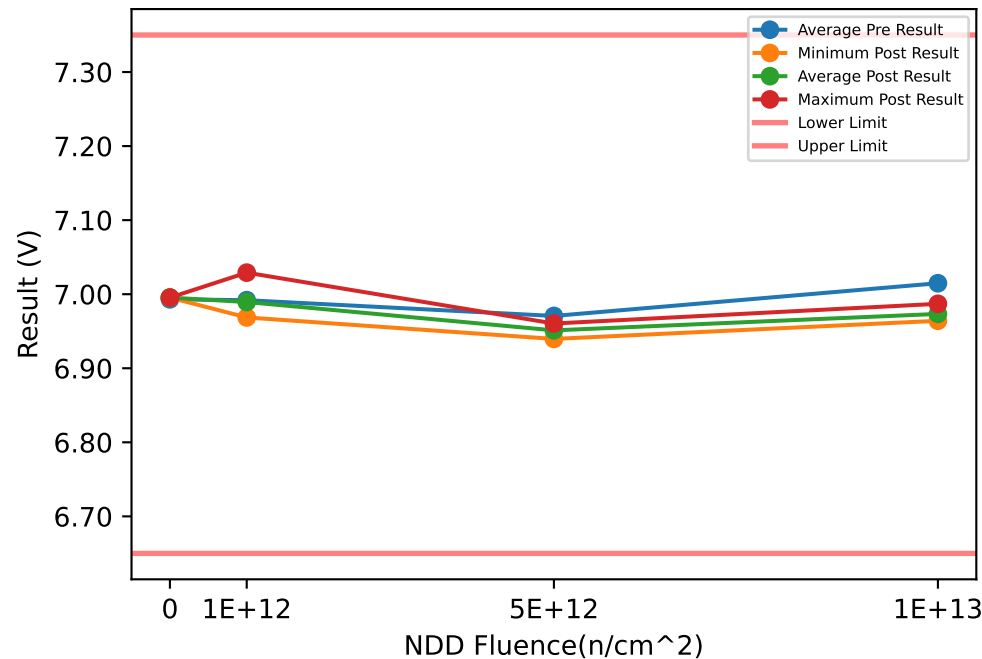


Test Statistics (V)

Fluence(n/cm ²)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9896	4.9896	4.9896		4.9897	4.9897	4.9897		0.0001	0.0001	0.0001	
1e+12	4.9835	4.9947	5.0007	0.0096811	4.9796	4.9912	4.9974	0.010027	-0.0039	-0.0035	-0.0033	0.00034641
5e+12	4.996	5.0019	5.0064	0.0053267	4.9774	4.9842	4.9892	0.0061175	-0.0186	-0.017633	-0.0171	0.00083865
1e+13	4.9858	5.0032	5.0183	0.016365	4.9523	4.9684	4.982	0.015007	-0.0363	-0.034767	-0.0335	0.0014189

Device Test: 60.21 V_BP7L(V_BP7L IIM 5MHz VIN_10V)

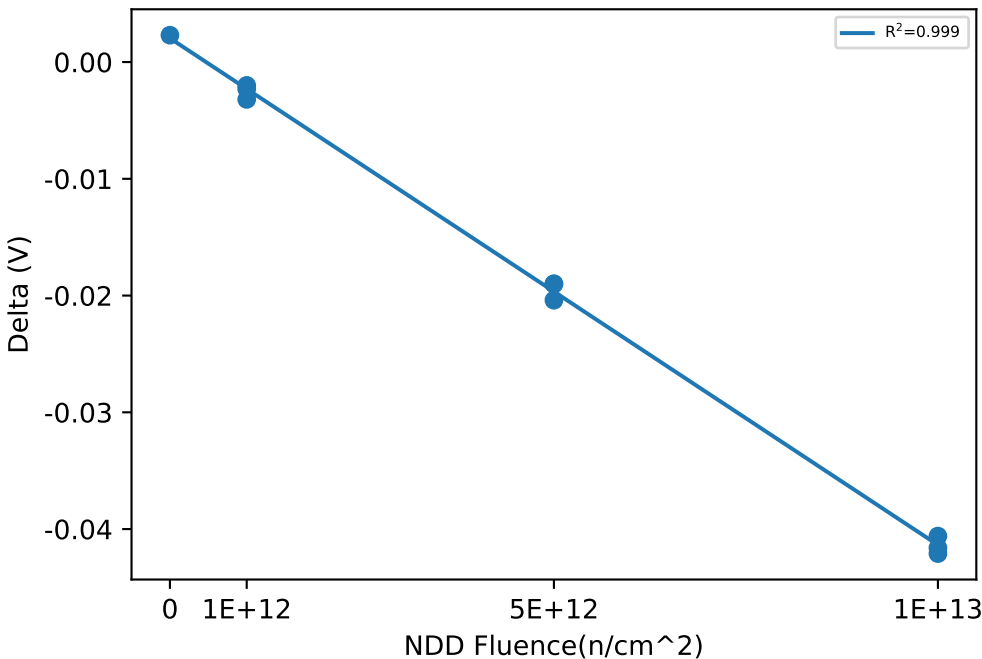
NDD vs Result Stats



Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	6.9726	6.9706	-0.002
551	1e+12	NDD	6.9709	6.9686	-0.0023
552	1e+12	NDD	7.0323	7.0291	-0.0032
553	5e+12	NDD	6.9794	6.9604	-0.019
554	5e+12	NDD	6.9739	6.9535	-0.0204
555	5e+12	NDD	6.9586	6.9396	-0.019
556	1e+13	NDD	7.0047	6.9641	-0.0406
557	1e+13	NDD	7.0286	6.987	-0.0416
558	1e+13	NDD	7.0111	6.969	-0.0421
559	0	NDD, Ctrl	6.9931	6.9954	0.0023

NDD vs Post - Pre Exposure Delta

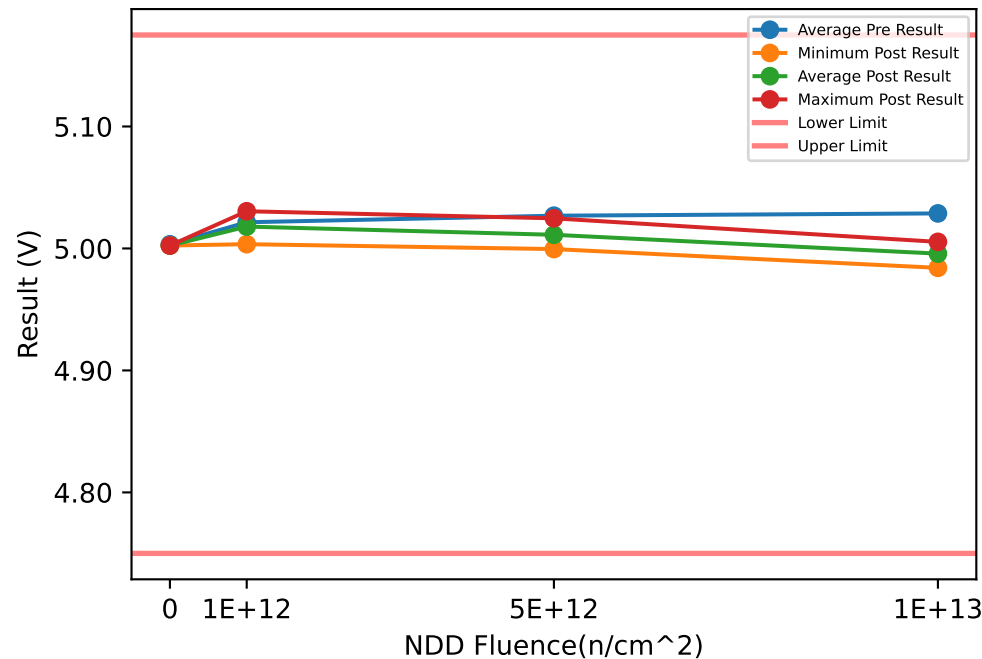


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.9931	6.9931	6.9931		6.9954	6.9954	6.9954		0.0023	0.0023	0.0023	
1e+12	6.9709	6.9919	7.0323	0.034969	6.9686	6.9894	7.0291	0.034367	-0.0032	-0.0025	-0.002	0.0006245
5e+12	6.9586	6.9706	6.9794	0.010778	6.9396	6.9512	6.9604	0.010594	-0.0204	-0.019467	-0.019	0.00080829
1e+13	7.0047	7.0148	7.0286	0.012372	6.9641	6.9734	6.987	0.012058	-0.0421	-0.041433	-0.0406	0.00076376

Device Test: 60.22 V_BP5L(V_BP5L IIM 5MHz VIN_10V)

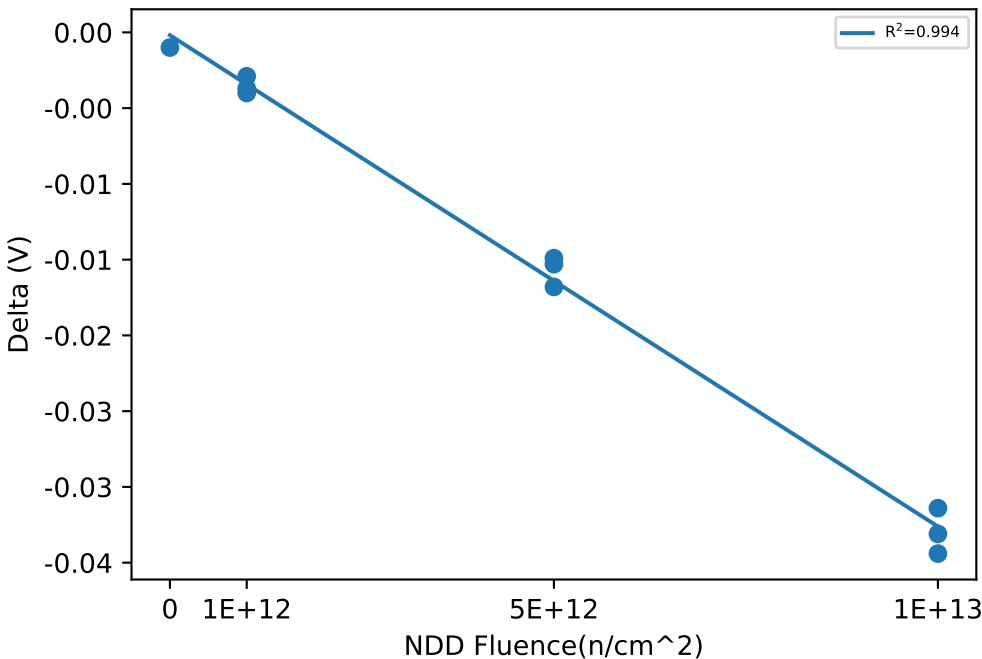
NDD vs Result Stats



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	5.0072	5.0035	-0.0037
551	1e+12	NDD	5.0238	5.0198	-0.004
552	1e+12	NDD	5.0334	5.0305	-0.0029
553	5e+12	NDD	5.0247	5.0094	-0.0153
554	5e+12	NDD	5.0163	4.9995	-0.0168
555	5e+12	NDD	5.0396	5.0247	-0.0149
556	1e+13	NDD	5.0172	4.9841	-0.0331
557	1e+13	NDD	5.0368	5.0054	-0.0314
558	1e+13	NDD	5.0322	4.9978	-0.0344
559	0	NDD, Ctrl	5.0034	5.0024	-0.001

NDD vs Post - Pre Exposure Delta

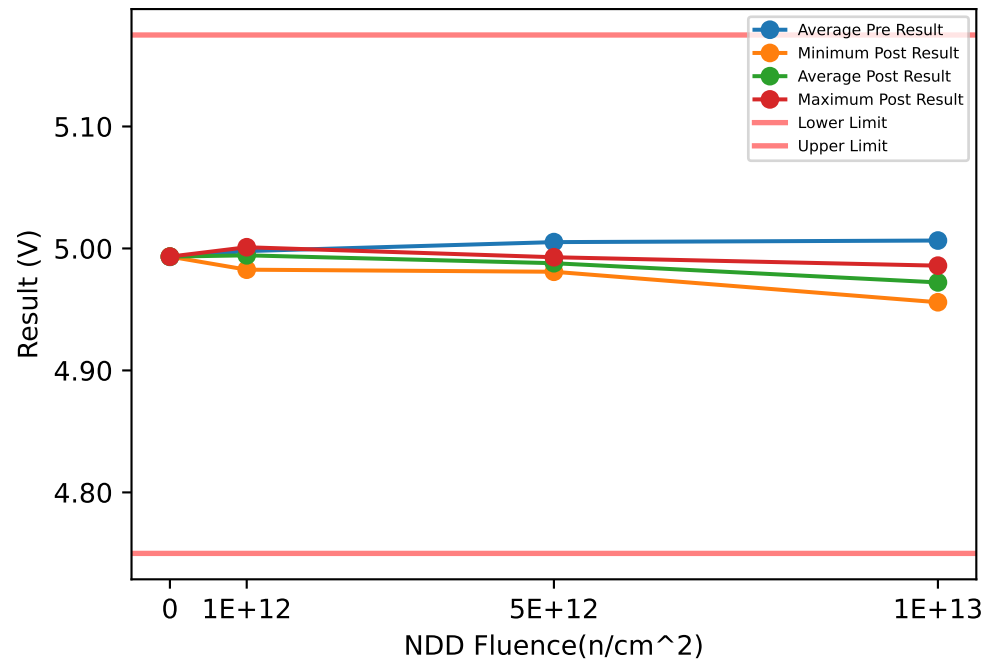


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0034	5.0034	5.0034		5.0024	5.0024	5.0024		-0.001	-0.001	-0.001	
1e+12	5.0072	5.0215	5.0334	0.013255	5.0035	5.0179	5.0305	0.013596	-0.004	-0.0035333	-0.0029	0.00056862
5e+12	5.0163	5.0269	5.0396	0.0118	4.9995	5.0112	5.0247	0.012696	-0.0168	-0.015667	-0.0149	0.0010017
1e+13	5.0172	5.0287	5.0368	0.01025	4.9841	4.9958	5.0054	0.010795	-0.0344	-0.032967	-0.0314	0.0015044

Device Test: 60.23 V_BP5H(V_BP5H IIM 5MHz VIN_10V)

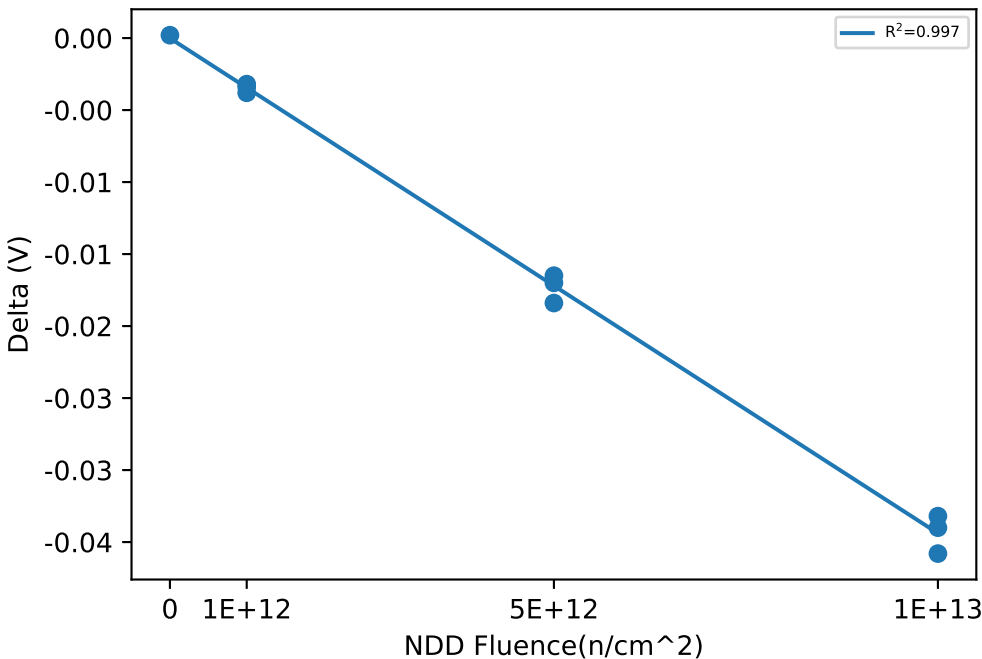
NDD vs Result Stats



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

Serial #	Fluence(n/cm ²)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.9864	4.9826	-0.0038
551	1e+12	NDD	5.0029	4.9995	-0.0034
552	1e+12	NDD	5.0042	5.001	-0.0032
553	5e+12	NDD	4.9993	4.9809	-0.0184
554	5e+12	NDD	5.0098	4.9928	-0.017
555	5e+12	NDD	5.0065	4.99	-0.0165
556	1e+13	NDD	4.9891	4.9559	-0.0332
557	1e+13	NDD	5.0217	4.9859	-0.0358
558	1e+13	NDD	5.0087	4.9747	-0.034
559	0	NDD, Ctrl	4.9931	4.9933	0.0002

NDD vs Post - Pre Exposure Delta

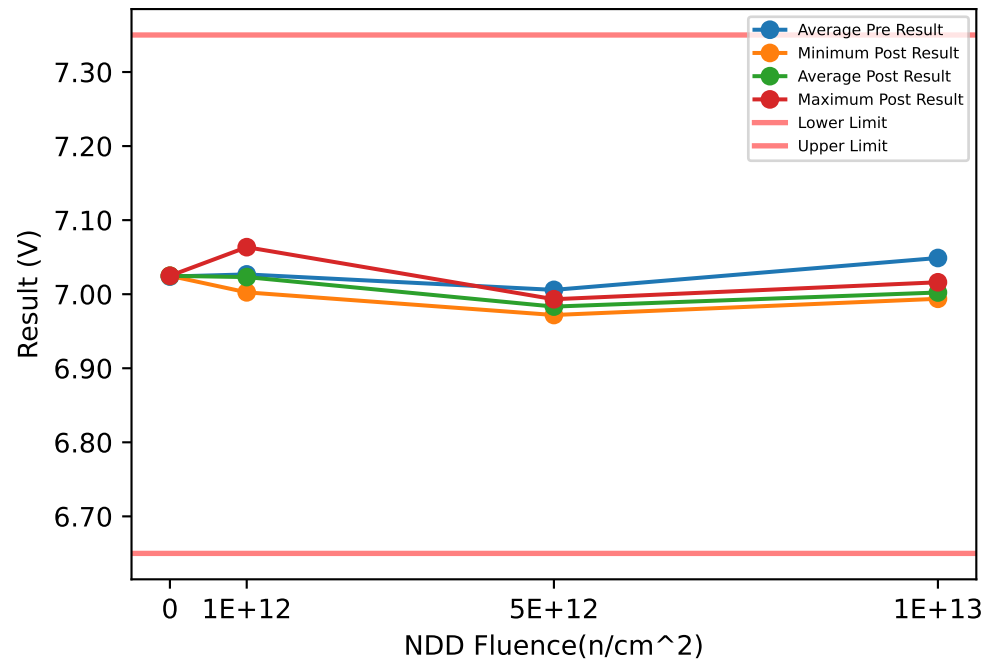


Test Statistics (V)

Fluence(n/cm ²)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9931	4.9931	4.9931		4.9933	4.9933	4.9933		0.0002	0.0002	0.0002	
1e+12	4.9864	4.9978	5.0042	0.0099229	4.9826	4.9944	5.001	0.010218	-0.0038	-0.0034667	-0.0032	0.00030551
5e+12	4.9993	5.0052	5.0098	0.0053694	4.9809	4.9879	4.9928	0.0062217	-0.0184	-0.0173	-0.0165	0.00098489
1e+13	4.9891	5.0065	5.0217	0.016411	4.9559	4.9722	4.9859	0.01516	-0.0358	-0.034333	-0.0332	0.0013317

Device Test: 60.3 V_BP7L(V_BP7L PWM 1MHz VIN_10V)

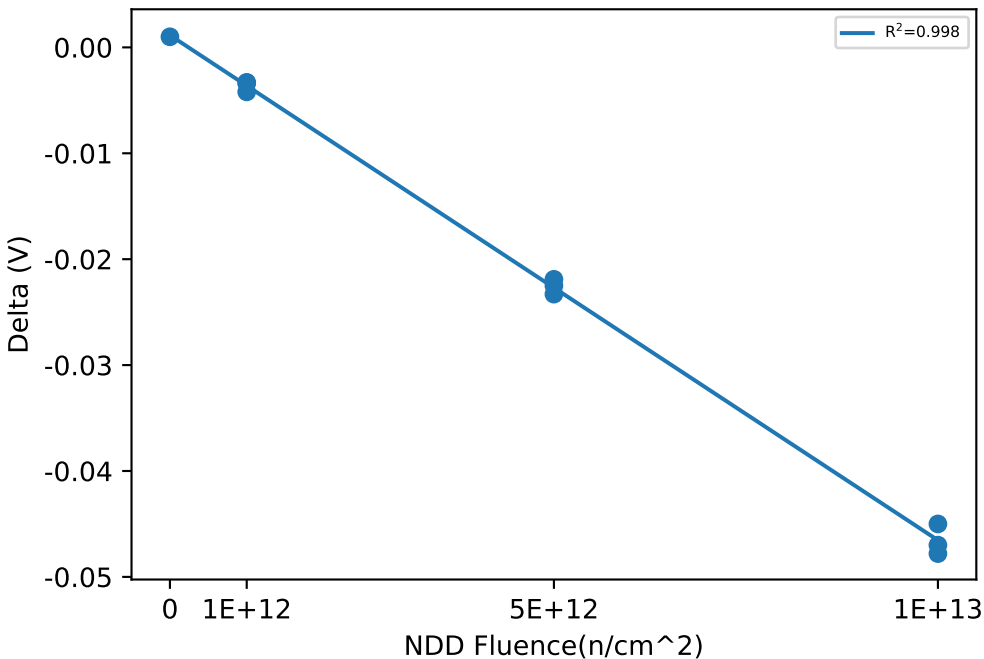
NDD vs Result Stats



Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	7.0059	7.0025	-0.0034
551	1e+12	NDD	7.0066	7.0033	-0.0033
552	1e+12	NDD	7.0677	7.0635	-0.0042
553	5e+12	NDD	7.0151	6.9932	-0.0219
554	5e+12	NDD	7.008	6.9847	-0.0233
555	5e+12	NDD	6.9944	6.9719	-0.0225
556	1e+13	NDD	7.0388	6.9938	-0.045
557	1e+13	NDD	7.0631	7.0161	-0.047
558	1e+13	NDD	7.0448	6.997	-0.0478
559	0	NDD, Ctrl	7.0238	7.0248	0.001

NDD vs Post - Pre Exposure Delta

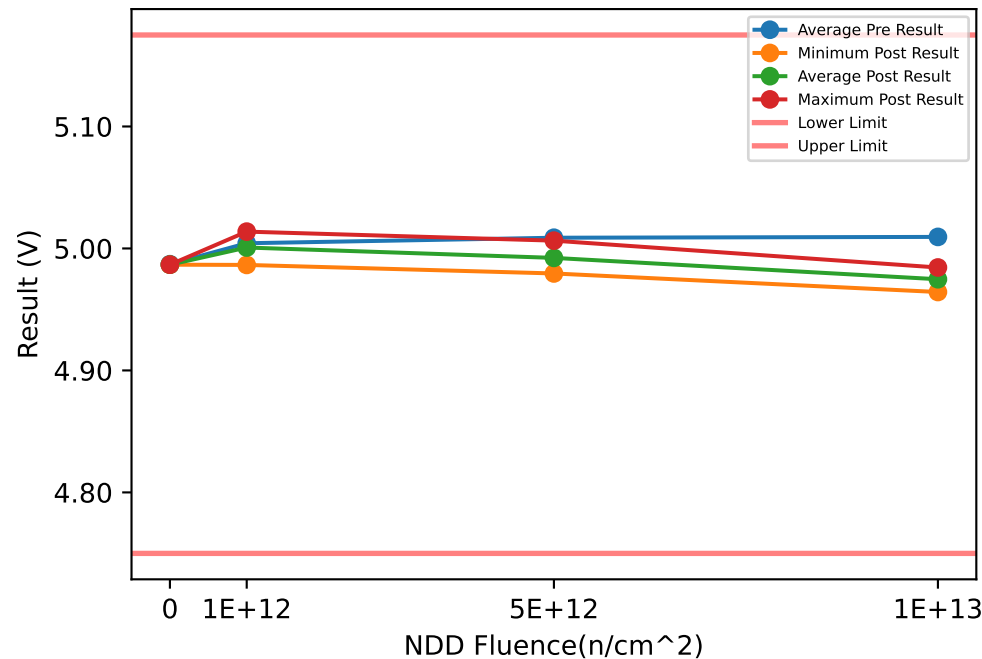


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0238	7.0238	7.0238		7.0248	7.0248	7.0248		0.001	0.001	0.001	
1e+12	7.0059	7.0267	7.0677	0.03548	7.0025	7.0231	7.0635	0.03499	-0.0042	-0.0036333	-0.0033	0.00049329
5e+12	6.9944	7.0058	7.0151	0.010519	6.9719	6.9833	6.9932	0.010722	-0.0233	-0.022567	-0.0219	0.00070238
1e+13	7.0388	7.0489	7.0631	0.012658	6.9938	7.0023	7.0161	0.012058	-0.0478	-0.0466	-0.045	0.0014422

Device Test: 60.4 V_BP5L(V_BP5L PWM 1MHz VIN_10V)

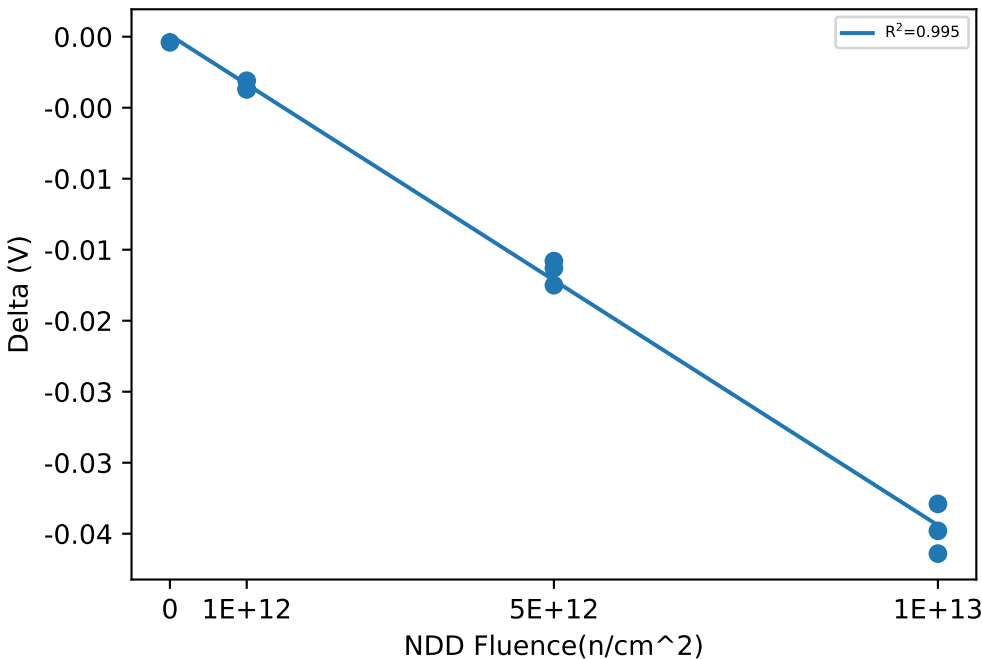
NDD vs Result Stats



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

Serial #	Fluence(n/cm ²)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.9902	4.9865	-0.0037
551	1e+12	NDD	5.0057	5.002	-0.0037
552	1e+12	NDD	5.0169	5.0138	-0.0031
553	5e+12	NDD	5.0067	4.9909	-0.0158
554	5e+12	NDD	4.997	4.9795	-0.0175
555	5e+12	NDD	5.0227	5.0064	-0.0163
556	1e+13	NDD	4.9991	4.9643	-0.0348
557	1e+13	NDD	5.0173	4.9844	-0.0329
558	1e+13	NDD	5.012	4.9756	-0.0364
559	0	NDD, Ctrl	4.9871	4.9867	-0.0004

NDD vs Post - Pre Exposure Delta

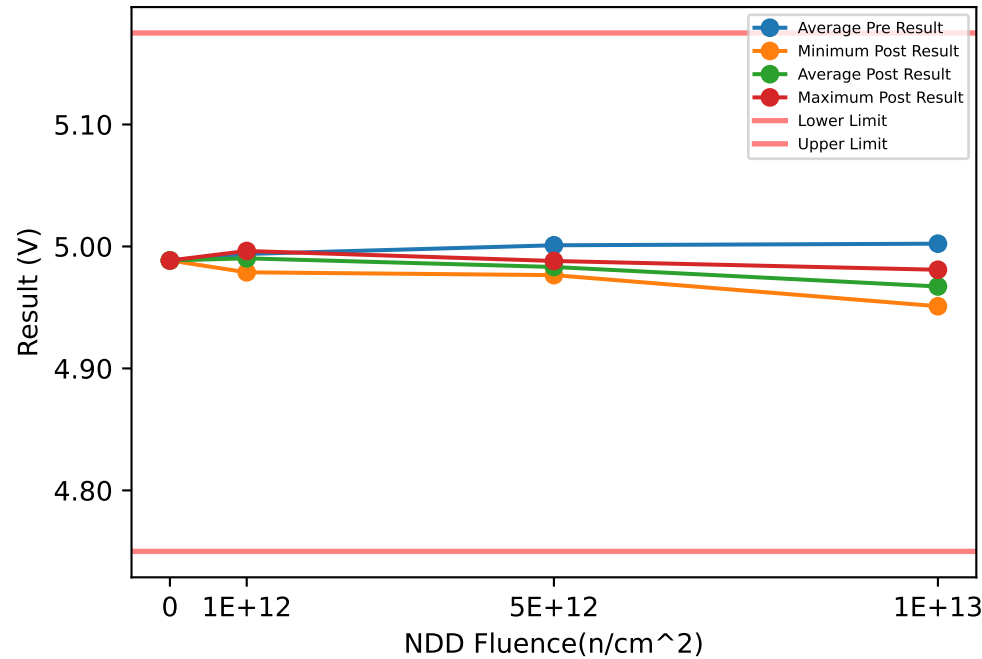


Test Statistics (V)

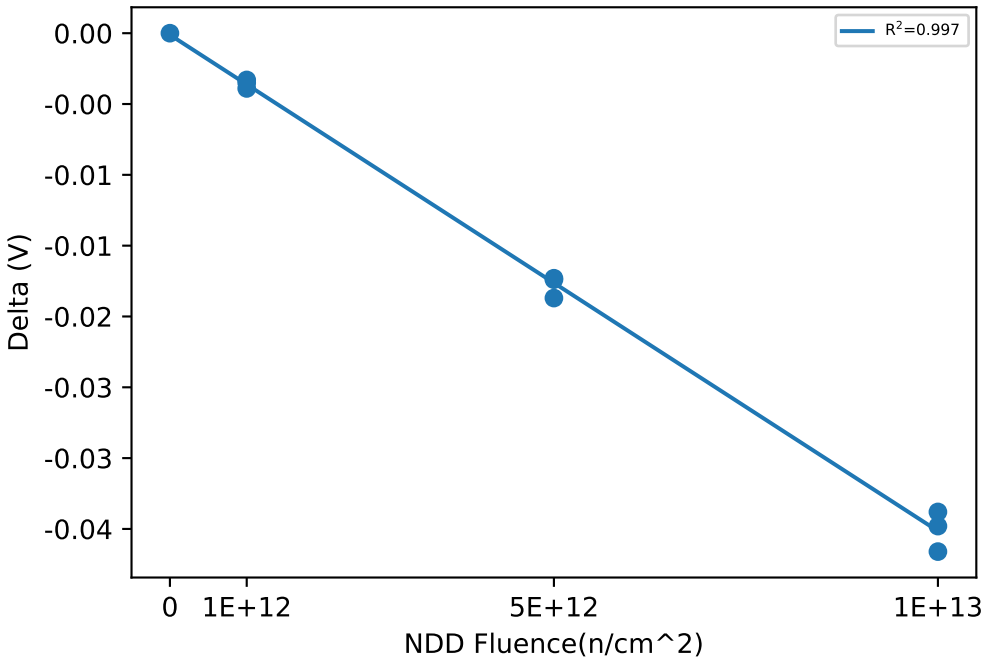
Fluence(n/cm ²)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9871	4.9871	4.9871		4.9867	4.9867	4.9867		-0.0004	-0.0004	-0.0004	
1e+12	4.9902	5.0043	5.0169	0.013408	4.9865	5.0008	5.0138	0.013692	-0.0037	-0.0035	-0.0031	0.00034641
5e+12	4.997	5.0088	5.0227	0.012978	4.9795	4.9923	5.0064	0.013502	-0.0175	-0.016533	-0.0158	0.00087369
1e+13	4.9991	5.0095	5.0173	0.0093607	4.9643	4.9748	4.9844	0.010076	-0.0364	-0.0347	-0.0329	0.0017521

Device Test: 60.5 V_BP5H(V_BP5H PWM 1MHz VIN_10V)

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

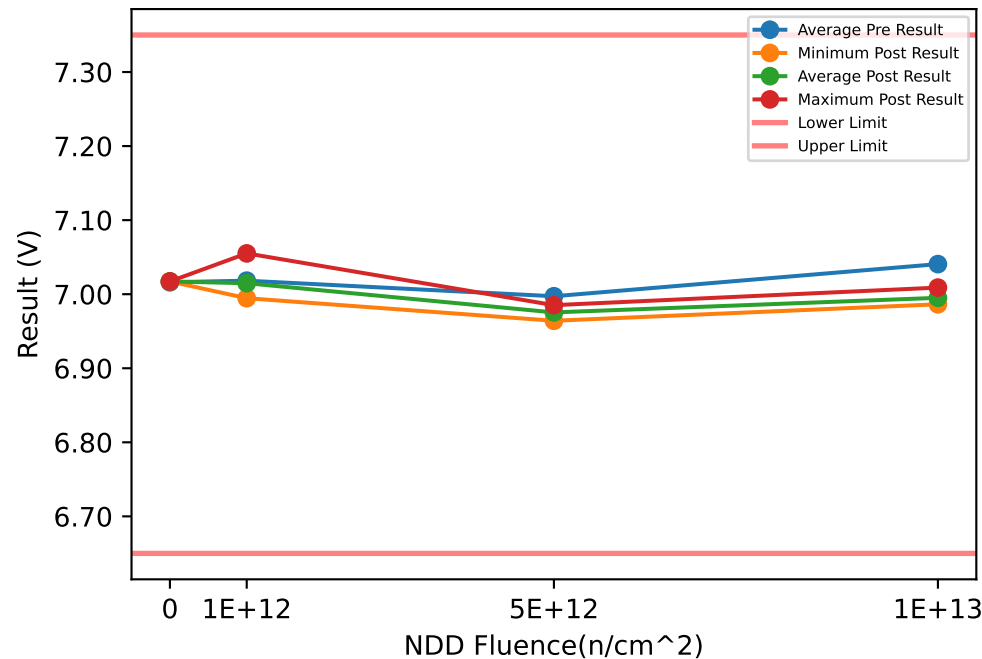
Serial #	Fluence(n/cm ²)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.9827	4.9788	-0.0039
551	1e+12	NDD	4.999	4.9957	-0.0033
552	1e+12	NDD	4.9998	4.9963	-0.0035
553	5e+12	NDD	4.9952	4.9765	-0.0187
554	5e+12	NDD	5.0055	4.9881	-0.0174
555	5e+12	NDD	5.0022	4.9849	-0.0173
556	1e+13	NDD	4.9848	4.951	-0.0338
557	1e+13	NDD	5.0175	4.9809	-0.0366
558	1e+13	NDD	5.0045	4.9697	-0.0348
559	0	NDD, Ctrl	4.9885	4.9885	0

Test Statistics (V)

Fluence(n/cm ²)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9885	4.9885	4.9885		4.9885	4.9885	4.9885		0	0	0	
1e+12	4.9827	4.9938	4.9998	0.00965	4.9788	4.9903	4.9963	0.009935	-0.0039	-0.0035667	-0.0033	0.00030551
5e+12	4.9952	5.001	5.0055	0.0052596	4.9765	4.9832	4.9881	0.0059911	-0.0187	-0.0178	-0.0173	0.00078102
1e+13	4.9848	5.0023	5.0175	0.016464	4.951	4.9672	4.9809	0.015106	-0.0366	-0.035067	-0.0338	0.0014189

Device Test: 60.6 V_BP7L(V_BP7L PWM 2MHz VIN_10V)

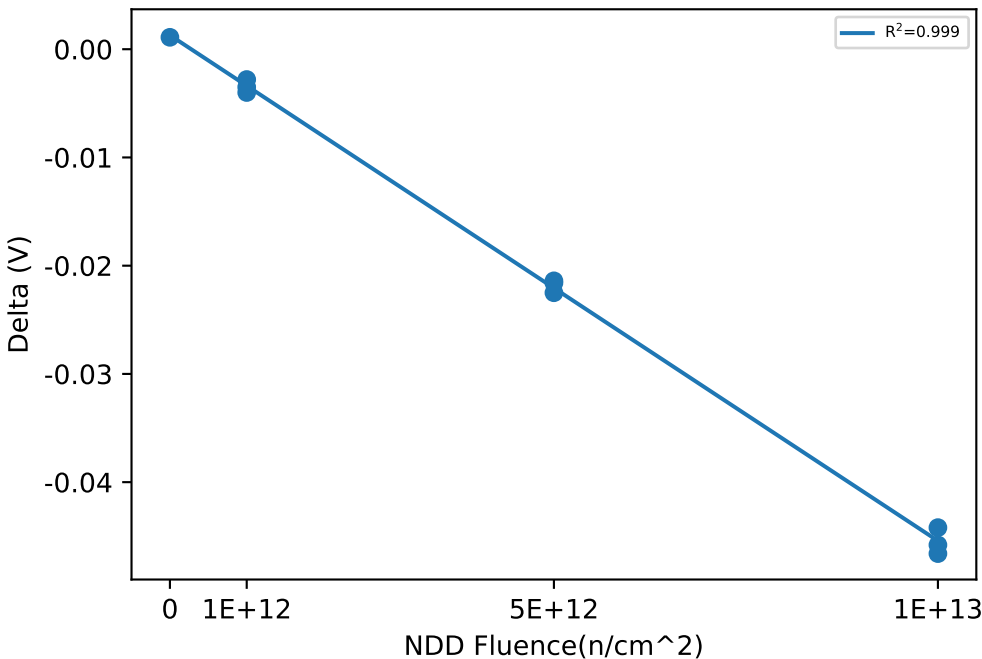
NDD vs Result Stats



Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	6.9976	6.9948	-0.0028
551	1e+12	NDD	6.9981	6.9946	-0.0035
552	1e+12	NDD	7.0591	7.0551	-0.004
553	5e+12	NDD	7.0066	6.9852	-0.0214
554	5e+12	NDD	6.9994	6.9769	-0.0225
555	5e+12	NDD	6.9857	6.9641	-0.0216
556	1e+13	NDD	7.0306	6.9864	-0.0442
557	1e+13	NDD	7.0547	7.0089	-0.0458
558	1e+13	NDD	7.0366	6.99	-0.0466
559	0	NDD, Ctrl	7.0161	7.0172	0.0011

NDD vs Post - Pre Exposure Delta

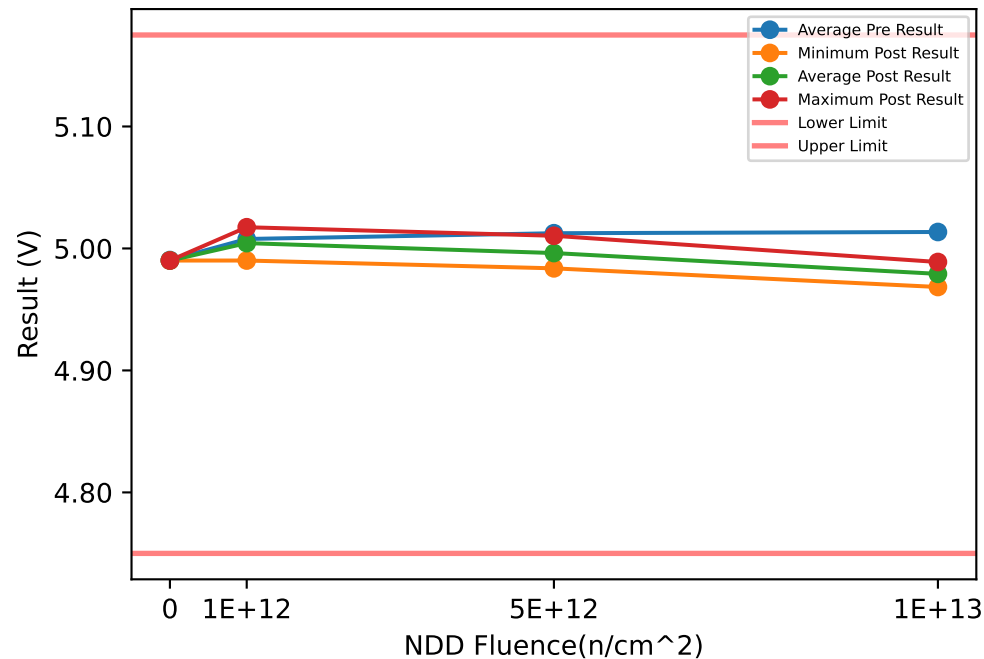


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0161	7.0161	7.0161		7.0172	7.0172	7.0172		0.0011	0.0011	0.0011	
1e+12	6.9976	7.0183	7.0591	0.035364	6.9946	7.0148	7.0551	0.034872	-0.004	-0.0034333	-0.0028	0.00060277
5e+12	6.9857	6.9972	7.0066	0.010617	6.9641	6.9754	6.9852	0.01063	-0.0225	-0.021833	-0.0214	0.00058595
1e+13	7.0306	7.0406	7.0547	0.012546	6.9864	6.9951	7.0089	0.012086	-0.0466	-0.045533	-0.0442	0.001222

Device Test: 60.7 V_BP5L(V_BP5L PWM 2MHz VIN_10V)

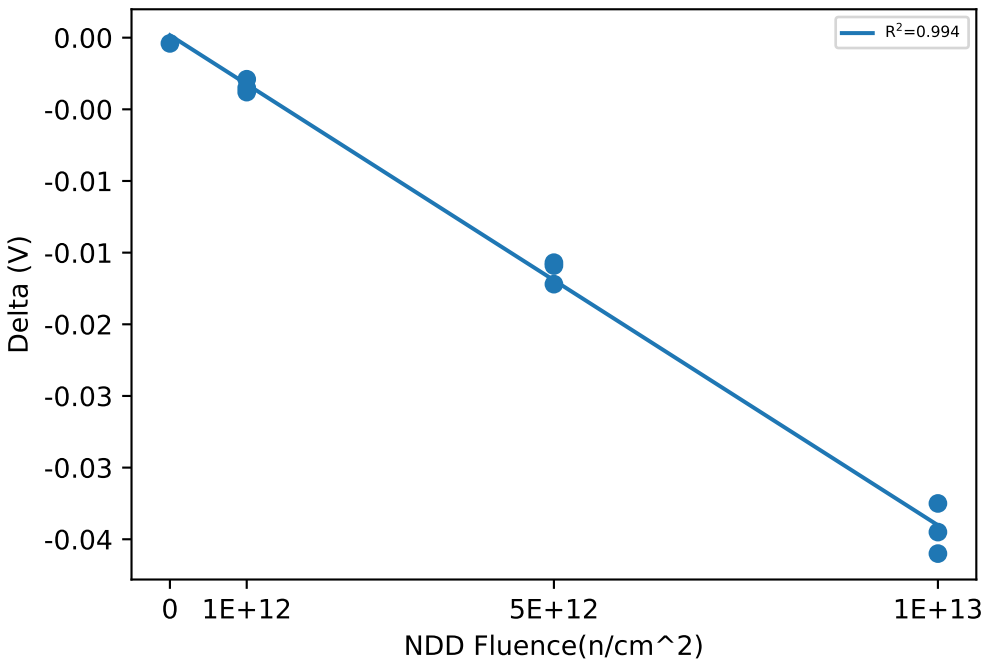
NDD vs Result Stats



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.9936	4.9901	-0.0035
551	1e+12	NDD	5.0094	5.0056	-0.0038
552	1e+12	NDD	5.0203	5.0174	-0.0029
553	5e+12	NDD	5.0103	4.9946	-0.0157
554	5e+12	NDD	5.0009	4.9837	-0.0172
555	5e+12	NDD	5.0263	5.0104	-0.0159
556	1e+13	NDD	5.0029	4.9684	-0.0345
557	1e+13	NDD	5.0214	4.9889	-0.0325
558	1e+13	NDD	5.0162	4.9802	-0.036
559	0	NDD, Ctrl	4.9905	4.9901	-0.0004

NDD vs Post - Pre Exposure Delta

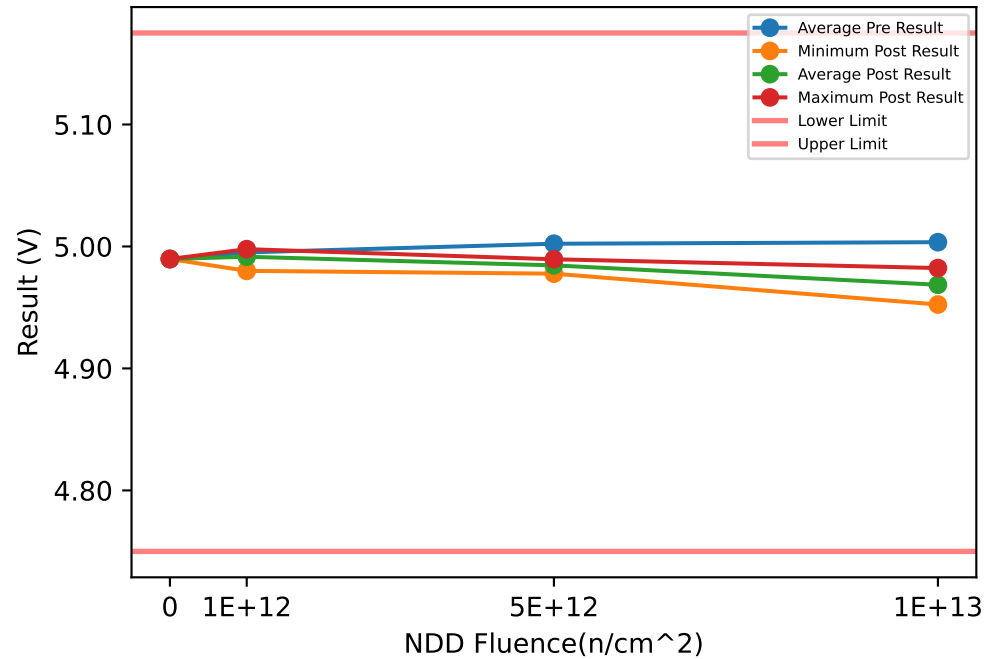


Test Statistics (V)

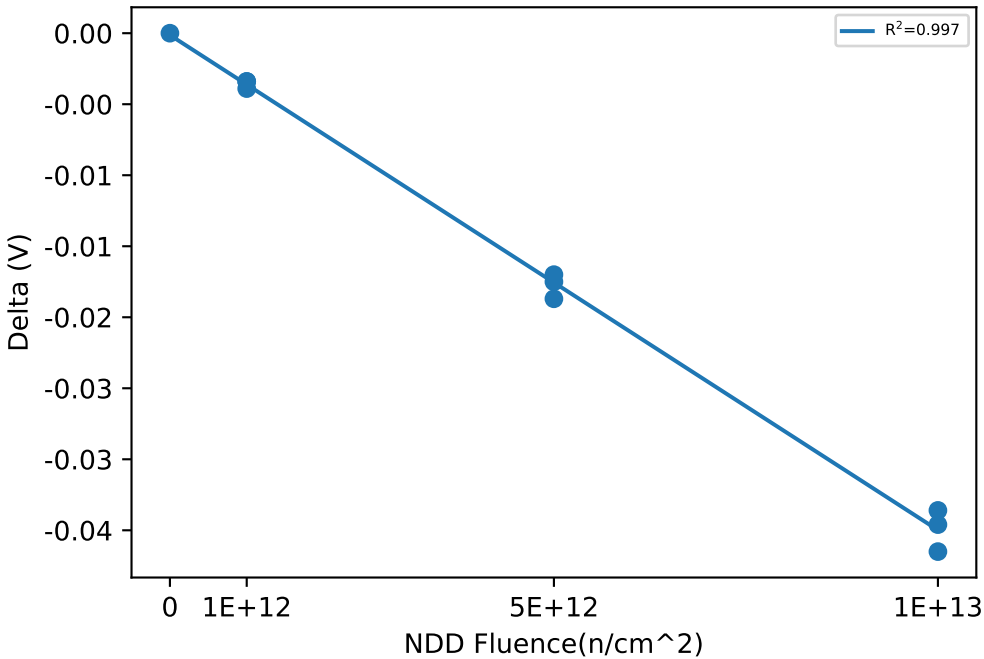
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9905	4.9905	4.9905		4.9901	4.9901	4.9901		-0.0004	-0.0004	-0.0004	
1e+12	4.9936	5.0078	5.0203	0.013425	4.9901	5.0044	5.0174	0.013692	-0.0038	-0.0034	-0.0029	0.00045826
5e+12	5.0009	5.0125	5.0263	0.012842	4.9837	4.9962	5.0104	0.013425	-0.0172	-0.016267	-0.0157	0.00081445
1e+13	5.0029	5.0135	5.0214	0.009541	4.9684	4.9792	4.9889	0.010289	-0.036	-0.034333	-0.0325	0.0017559

Device Test: 60.8 V_BP5H(V_BP5H PWM 2MHz VIN_10V)

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

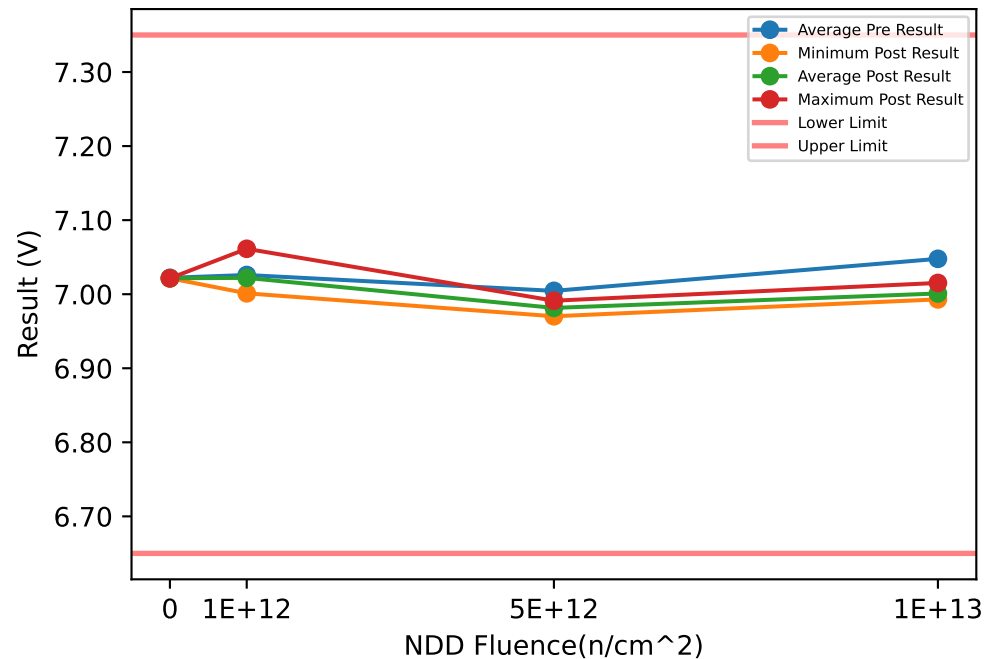
Serial #	Fluence(n/cm ²)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.9839	4.98	-0.0039
551	1e+12	NDD	5.0003	4.9969	-0.0034
552	1e+12	NDD	5.0012	4.9978	-0.0034
553	5e+12	NDD	4.9964	4.9777	-0.0187
554	5e+12	NDD	5.007	4.9895	-0.0175
555	5e+12	NDD	5.0033	4.9863	-0.017
556	1e+13	NDD	4.986	4.9524	-0.0336
557	1e+13	NDD	5.0188	4.9823	-0.0365
558	1e+13	NDD	5.0057	4.9711	-0.0346
559	0	NDD, Ctrl	4.9897	4.9897	0

Test Statistics (V)

Fluence(n/cm ²)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9897	4.9897	4.9897		4.9897	4.9897	4.9897		0	0	0	
1e+12	4.9839	4.9951	5.0012	0.0097388	4.98	4.9916	4.9978	0.010027	-0.0039	-0.0035667	-0.0034	0.00028868
5e+12	4.9964	5.0022	5.007	0.0053799	4.9777	4.9845	4.9895	0.0061025	-0.0187	-0.017733	-0.017	0.00087369
1e+13	4.986	5.0035	5.0188	0.01651	4.9524	4.9686	4.9823	0.015106	-0.0365	-0.0349	-0.0336	0.0014731

Device Test: 60.9 V_BP7L(V_BP7L PWM 5MHz VIN_10V)

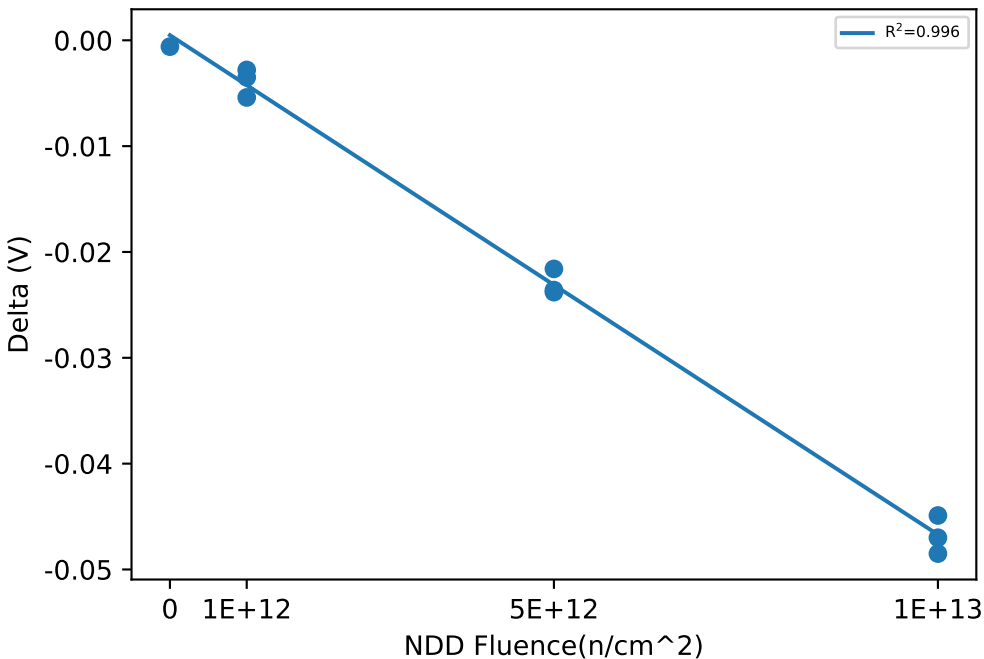
NDD vs Result Stats



Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	7.0047	7.0012	-0.0035
551	1e+12	NDD	7.0064	7.0036	-0.0028
552	1e+12	NDD	7.0667	7.0613	-0.0054
553	5e+12	NDD	7.0128	6.9912	-0.0216
554	5e+12	NDD	7.0067	6.9831	-0.0236
555	5e+12	NDD	6.994	6.9702	-0.0238
556	1e+13	NDD	7.0379	6.993	-0.0449
557	1e+13	NDD	7.0622	7.0152	-0.047
558	1e+13	NDD	7.0432	6.9947	-0.0485
559	0	NDD, Ctrl	7.0221	7.0215	-0.0006

NDD vs Post - Pre Exposure Delta

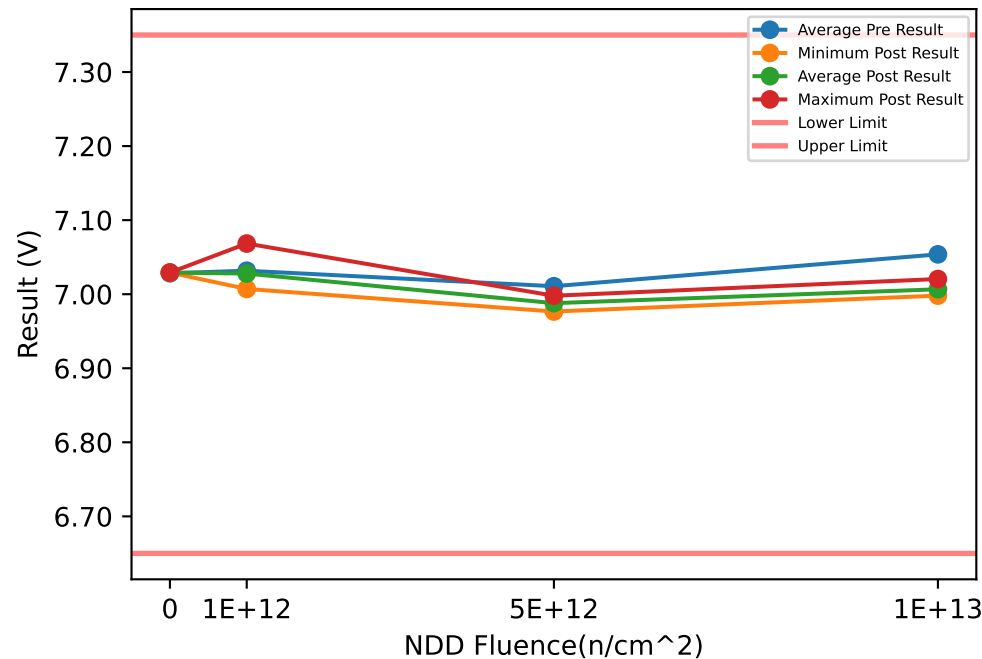


Test Statistics (V)

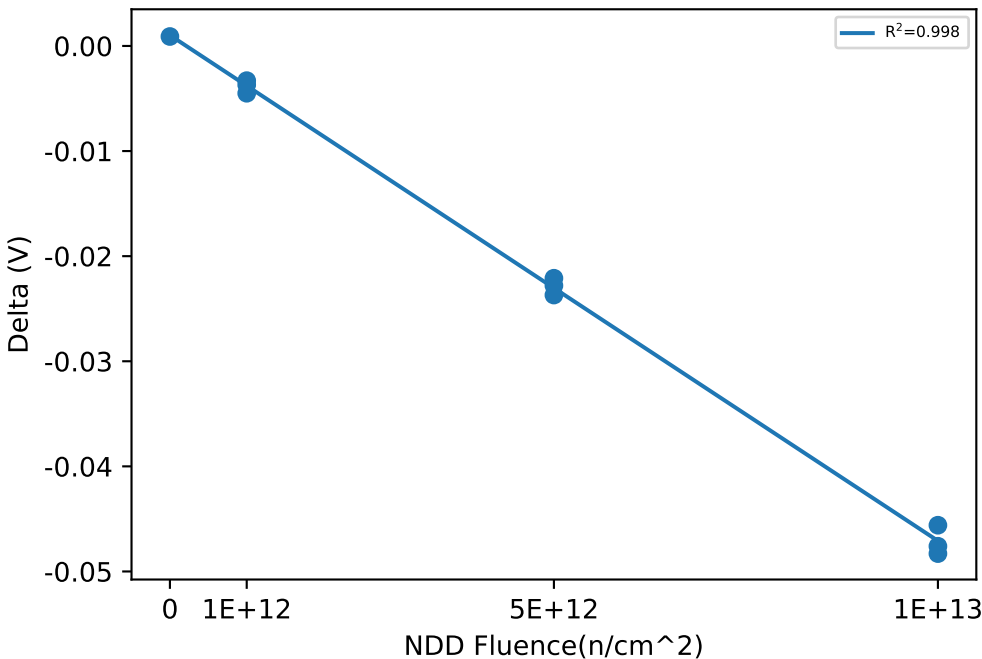
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0221	7.0221	7.0221		7.0215	7.0215	7.0215		-0.0006	-0.0006	-0.0006	
1e+12	7.0047	7.0259	7.0667	0.035315	7.0012	7.022	7.0613	0.034027	-0.0054	-0.0039	-0.0028	0.0013454
5e+12	6.994	7.0045	7.0128	0.0095911	6.9702	6.9815	6.9912	0.010591	-0.0238	-0.023	-0.0216	0.0012166
1e+13	7.0379	7.0478	7.0622	0.012777	6.993	7.001	7.0152	0.012356	-0.0485	-0.0468	-0.0449	0.0018083

Device Test: 61.0 V_BP7L(V_BP7L PWM 500kHz VIN_12V)

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

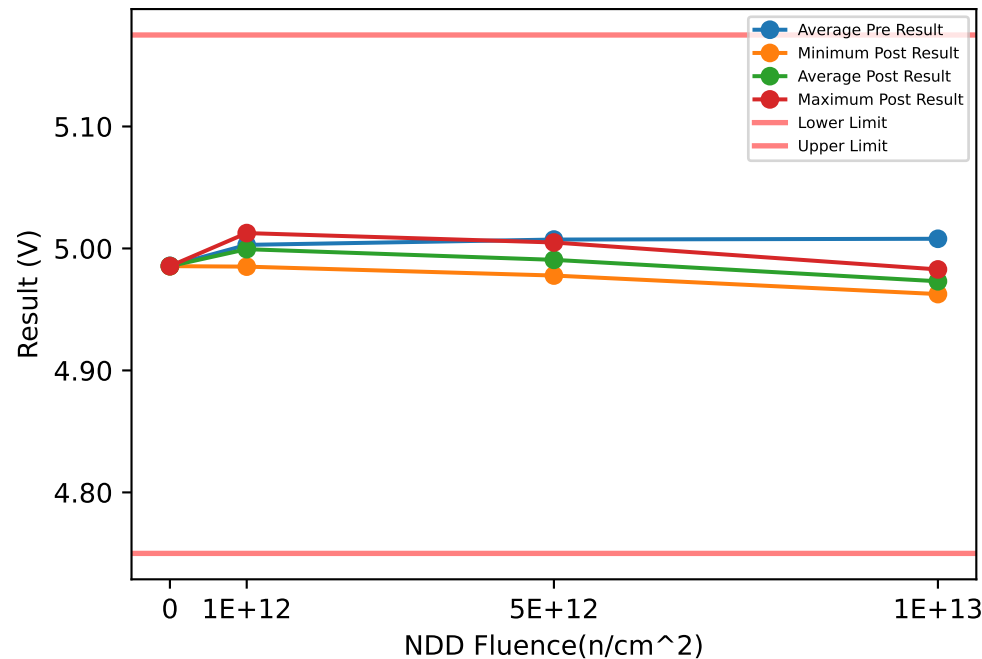
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	7.0104	7.0071	-0.0033
551	1e+12	NDD	7.0118	7.0081	-0.0037
552	1e+12	NDD	7.0729	7.0684	-0.0045
553	5e+12	NDD	7.02	6.9979	-0.0221
554	5e+12	NDD	7.0129	6.9892	-0.0237
555	5e+12	NDD	6.9994	6.9766	-0.0228
556	1e+13	NDD	7.0437	6.9981	-0.0456
557	1e+13	NDD	7.0681	7.0205	-0.0476
558	1e+13	NDD	7.0496	7.0013	-0.0483
559	0	NDD, Ctrl	7.0283	7.0292	0.0009

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0283	7.0283	7.0283		7.0292	7.0292	7.0292		0.0009	0.0009	0.0009	
1e+12	7.0104	7.0317	7.0729	0.035687	7.0071	7.0279	7.0684	0.035106	-0.0045	-0.0038333	-0.0033	0.00061101
5e+12	6.9994	7.0108	7.02	0.010464	6.9766	6.9879	6.9979	0.010709	-0.0237	-0.022867	-0.0221	0.00080208
1e+13	7.0437	7.0538	7.0681	0.012731	6.9981	7.0066	7.0205	0.012115	-0.0483	-0.047167	-0.0456	0.0014012

Device Test: 61.1 V_BP5L(V_BP5L PWM 500kHz VIN_12V)

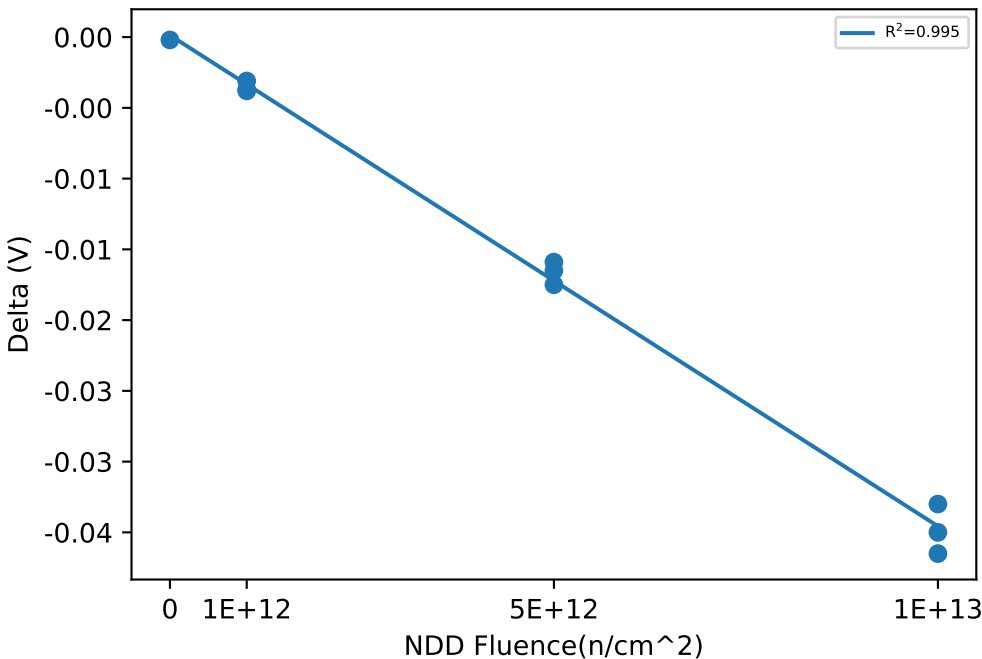
NDD vs Result Stats



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.9888	4.9851	-0.0037
551	1e+12	NDD	5.0043	5.0005	-0.0038
552	1e+12	NDD	5.0157	5.0126	-0.0031
553	5e+12	NDD	5.0052	4.9893	-0.0159
554	5e+12	NDD	4.9953	4.9778	-0.0175
555	5e+12	NDD	5.0214	5.0049	-0.0165
556	1e+13	NDD	4.9976	4.9626	-0.035
557	1e+13	NDD	5.0158	4.9828	-0.033
558	1e+13	NDD	5.0104	4.9739	-0.0365
559	0	NDD, Ctrl	4.9857	4.9855	-0.0002

NDD vs Post - Pre Exposure Delta

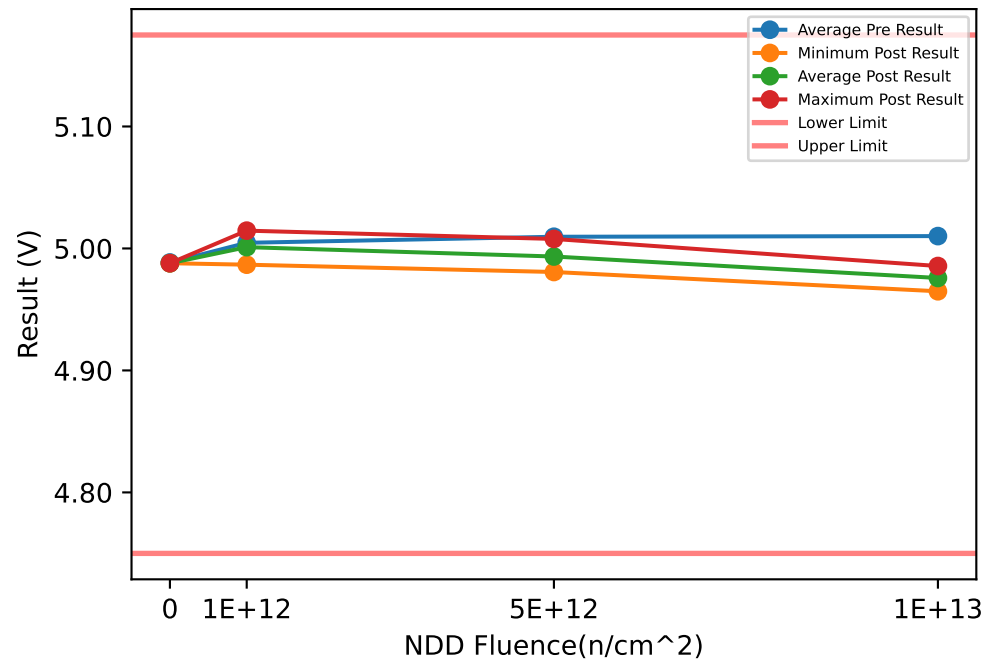


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9857	4.9857	4.9857		4.9855	4.9855	4.9855		-0.0002	-0.0002	-0.0002	
1e+12	4.9888	5.0029	5.0157	0.013502	4.9851	4.9994	5.0126	0.013783	-0.0038	-0.0035333	-0.0031	0.00037859
5e+12	4.9953	5.0073	5.0214	0.013176	4.9778	4.9907	5.0049	0.013602	-0.0175	-0.016633	-0.0159	0.00080829
1e+13	4.9976	5.0079	5.0158	0.0093474	4.9626	4.9731	4.9828	0.010124	-0.0365	-0.034833	-0.033	0.0017559

Device Test: 61.10 V_BP5L(V_BP5L PWM 5MHz VIN_12V)

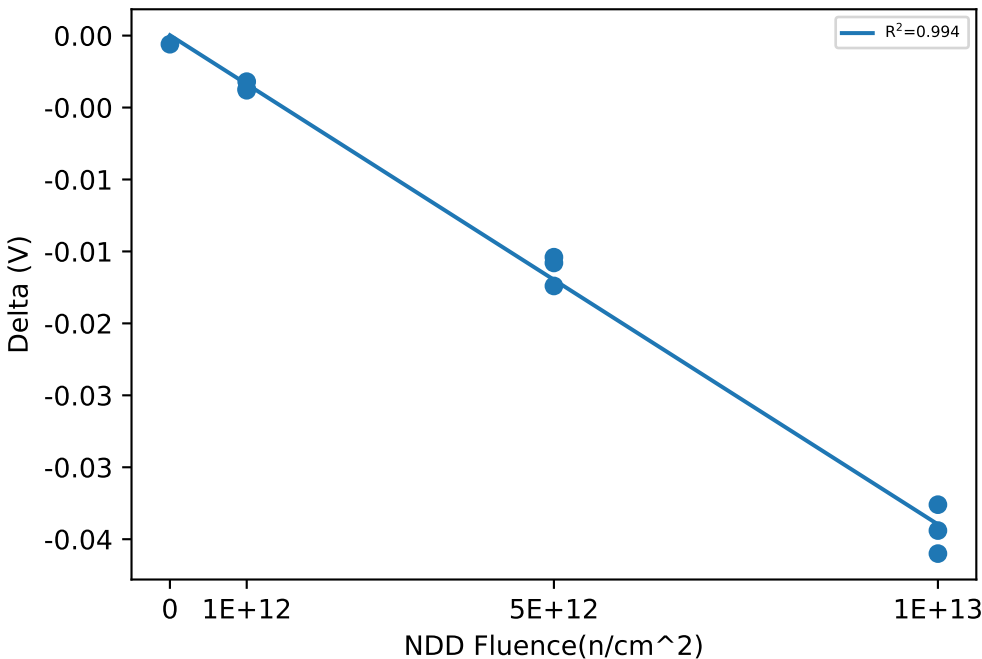
NDD vs Result Stats



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.9904	4.9867	-0.0037
551	1e+12	NDD	5.0057	5.0019	-0.0038
552	1e+12	NDD	5.0178	5.0146	-0.0032
553	5e+12	NDD	5.0071	4.9917	-0.0154
554	5e+12	NDD	4.9981	4.9807	-0.0174
555	5e+12	NDD	5.0236	5.0078	-0.0158
556	1e+13	NDD	4.9993	4.9649	-0.0344
557	1e+13	NDD	5.0182	4.9856	-0.0326
558	1e+13	NDD	5.0129	4.9769	-0.036
559	0	NDD, Ctrl	4.9885	4.9879	-0.0006

NDD vs Post - Pre Exposure Delta

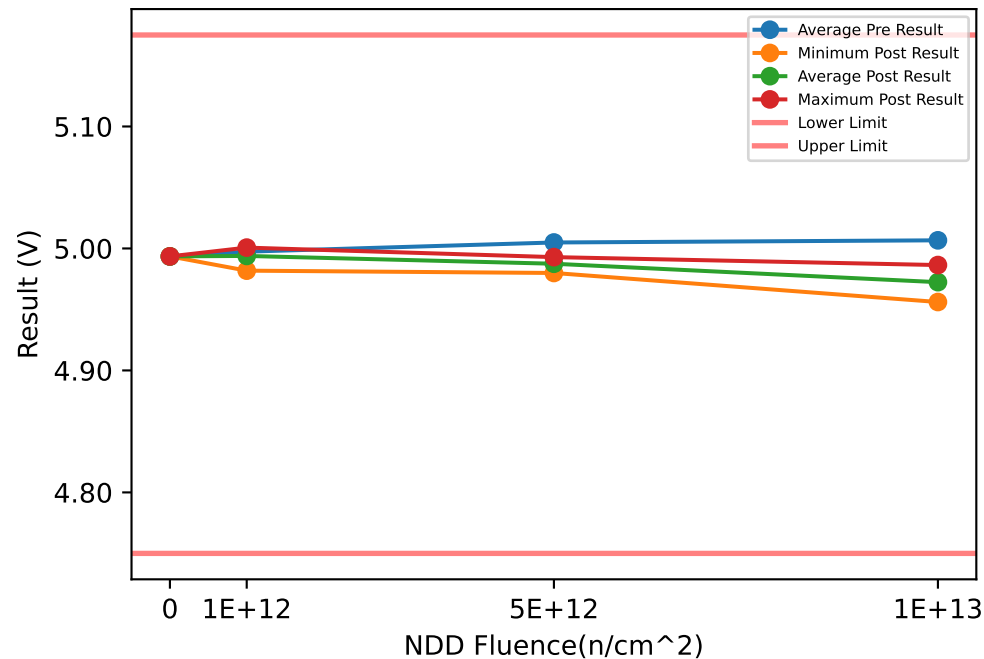


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9885	4.9885	4.9885		4.9879	4.9879	4.9879		-0.0006	-0.0006	-0.0006	
1e+12	4.9904	5.0046	5.0178	0.013731	4.9867	5.0011	5.0146	0.013969	-0.0038	-0.0035667	-0.0032	0.00032146
5e+12	4.9981	5.0096	5.0236	0.012933	4.9807	4.9934	5.0078	0.01363	-0.0174	-0.0162	-0.0154	0.0010583
1e+13	4.9993	5.0101	5.0182	0.009749	4.9649	4.9758	4.9856	0.010394	-0.036	-0.034333	-0.0326	0.001701

Device Test: 61.11 V_BP5H(V_BP5H PWM 5MHz VIN_12V)

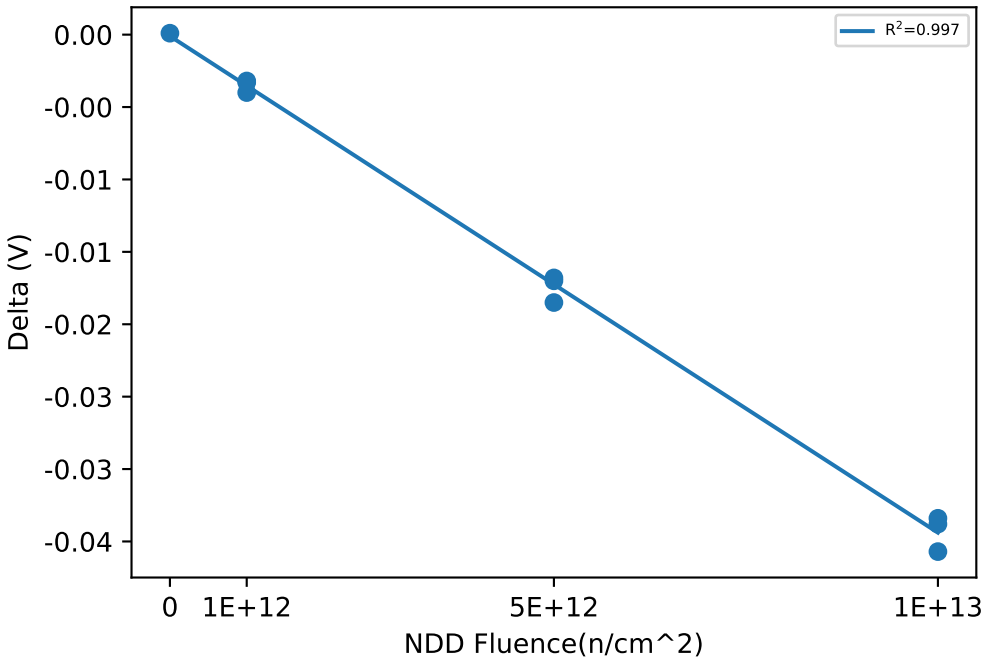
NDD vs Result Stats



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.9858	4.9818	-0.004
551	1e+12	NDD	5.0023	4.9991	-0.0032
552	1e+12	NDD	5.004	5.0007	-0.0033
553	5e+12	NDD	4.9984	4.9799	-0.0185
554	5e+12	NDD	5.0099	4.9929	-0.017
555	5e+12	NDD	5.0064	4.9896	-0.0168
556	1e+13	NDD	4.9895	4.9561	-0.0334
557	1e+13	NDD	5.0221	4.9864	-0.0357
558	1e+13	NDD	5.0084	4.9746	-0.0338
559	0	NDD, Ctrl	4.9934	4.9935	0.0001

NDD vs Post - Pre Exposure Delta

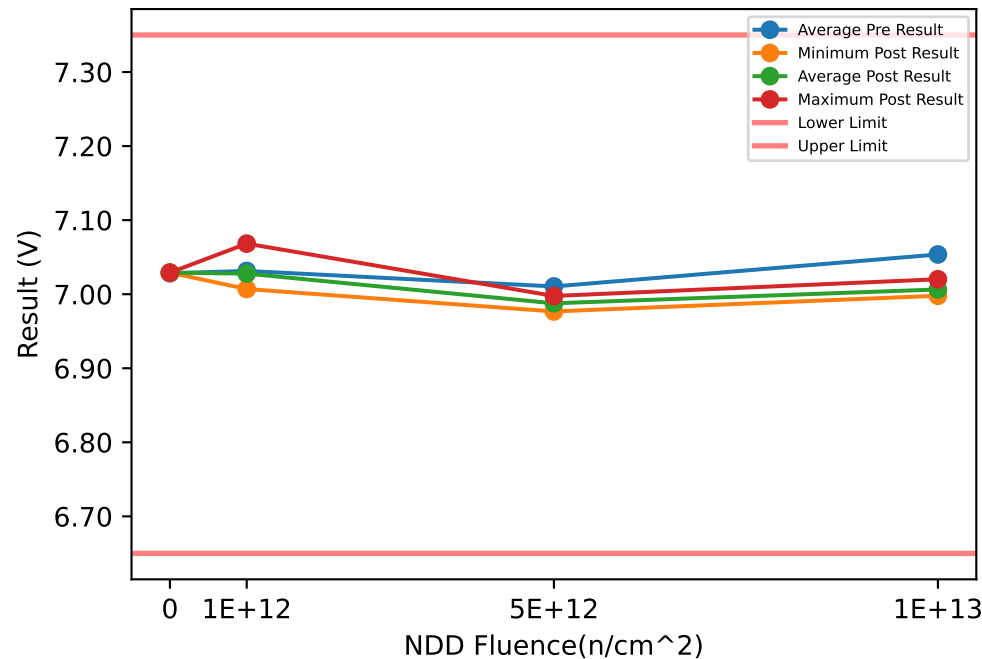


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9934	4.9934	4.9934		4.9935	4.9935	4.9935		0.0001	0.0001	0.0001	
1e+12	4.9858	4.9974	5.004	0.010053	4.9818	4.9939	5.0007	0.010481	-0.004	-0.0035	-0.0032	0.00043589
5e+12	4.9984	5.0049	5.0099	0.0058949	4.9799	4.9875	4.9929	0.0067575	-0.0185	-0.017433	-0.0168	0.00092916
1e+13	4.9895	5.0067	5.0221	0.016369	4.9561	4.9724	4.9864	0.015273	-0.0357	-0.0343	-0.0334	0.0012288

Device Test: 61.12 V_BP7L(V_BP7L IIM 500kHz VIN_12V)

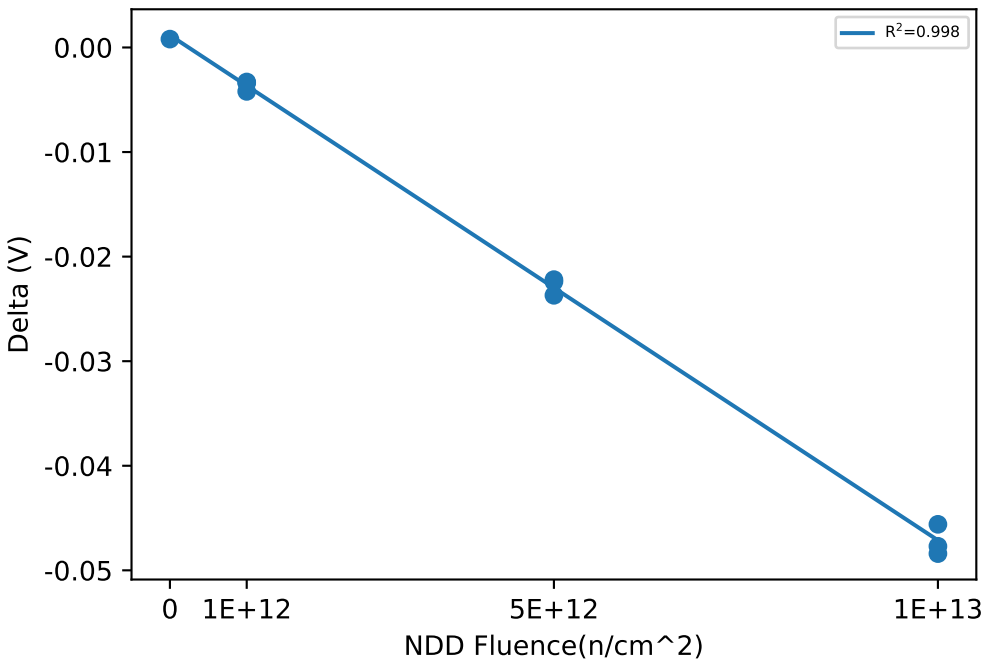
NDD vs Result Stats



Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	7.0103	7.007	-0.0033
551	1e+12	NDD	7.0114	7.008	-0.0034
552	1e+12	NDD	7.0725	7.0683	-0.0042
553	5e+12	NDD	7.0198	6.9976	-0.0222
554	5e+12	NDD	7.0125	6.9888	-0.0237
555	5e+12	NDD	6.9991	6.9767	-0.0224
556	1e+13	NDD	7.0435	6.9979	-0.0456
557	1e+13	NDD	7.0679	7.0202	-0.0477
558	1e+13	NDD	7.0495	7.0011	-0.0484
559	0	NDD, Ctrl	7.0283	7.0291	0.0008

NDD vs Post - Pre Exposure Delta

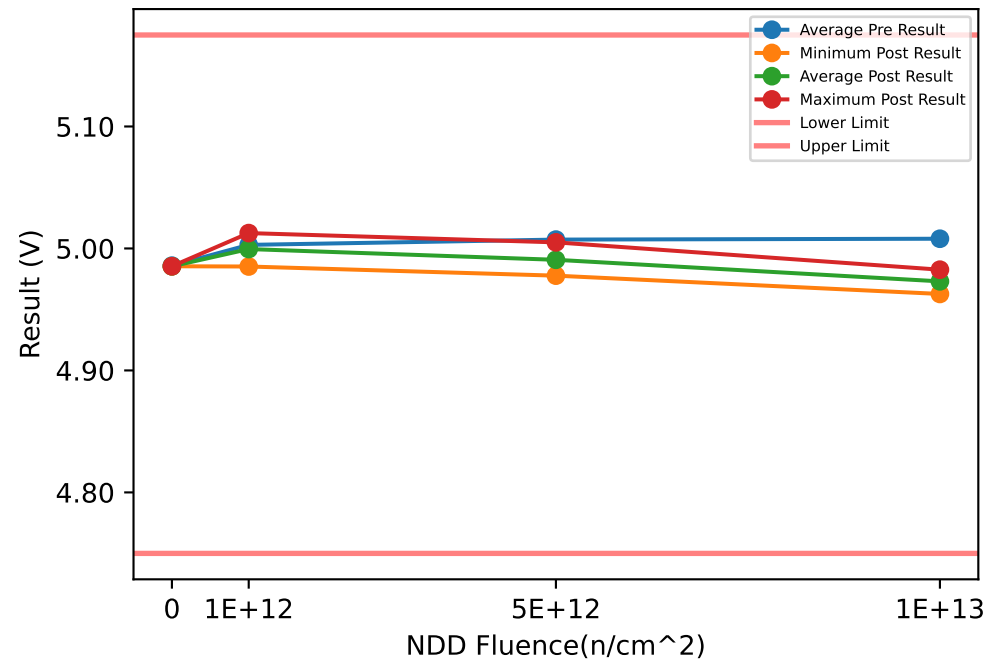


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0283	7.0283	7.0283		7.0291	7.0291	7.0291		0.0008	0.0008	0.0008	
1e+12	7.0103	7.0314	7.0725	0.035598	7.007	7.0278	7.0683	0.035106	-0.0042	-0.0036333	-0.0033	0.00049329
5e+12	6.9991	7.0105	7.0198	0.010499	6.9767	6.9877	6.9976	0.010493	-0.0237	-0.022767	-0.0222	0.00081445
1e+13	7.0435	7.0536	7.0679	0.012714	6.9979	7.0064	7.0202	0.012058	-0.0484	-0.047233	-0.0456	0.0014572

Device Test: 61.13 V_BP5L(V_BP5L IIM 500kHz VIN_12V)

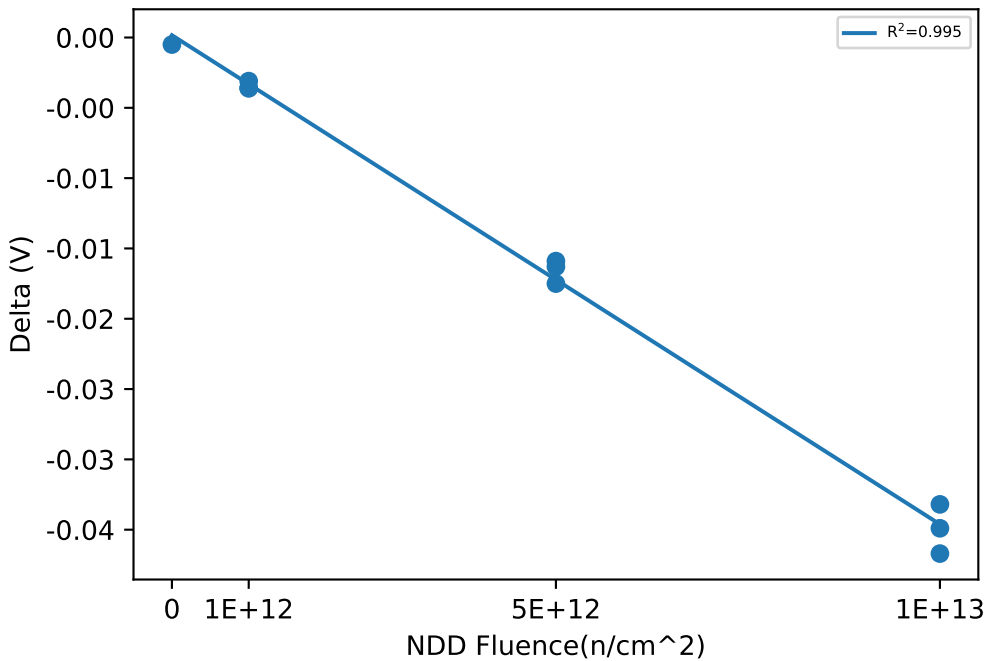
NDD vs Result Stats



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.9888	4.9852	-0.0036
551	1e+12	NDD	5.0043	5.0007	-0.0036
552	1e+12	NDD	5.0157	5.0126	-0.0031
553	5e+12	NDD	5.0053	4.9894	-0.0159
554	5e+12	NDD	4.9952	4.9777	-0.0175
555	5e+12	NDD	5.0213	5.005	-0.0163
556	1e+13	NDD	4.9976	4.9627	-0.0349
557	1e+13	NDD	5.0158	4.9826	-0.0332
558	1e+13	NDD	5.0105	4.9738	-0.0367
559	0	NDD, Ctrl	4.9859	4.9854	-0.0005

NDD vs Post - Pre Exposure Delta

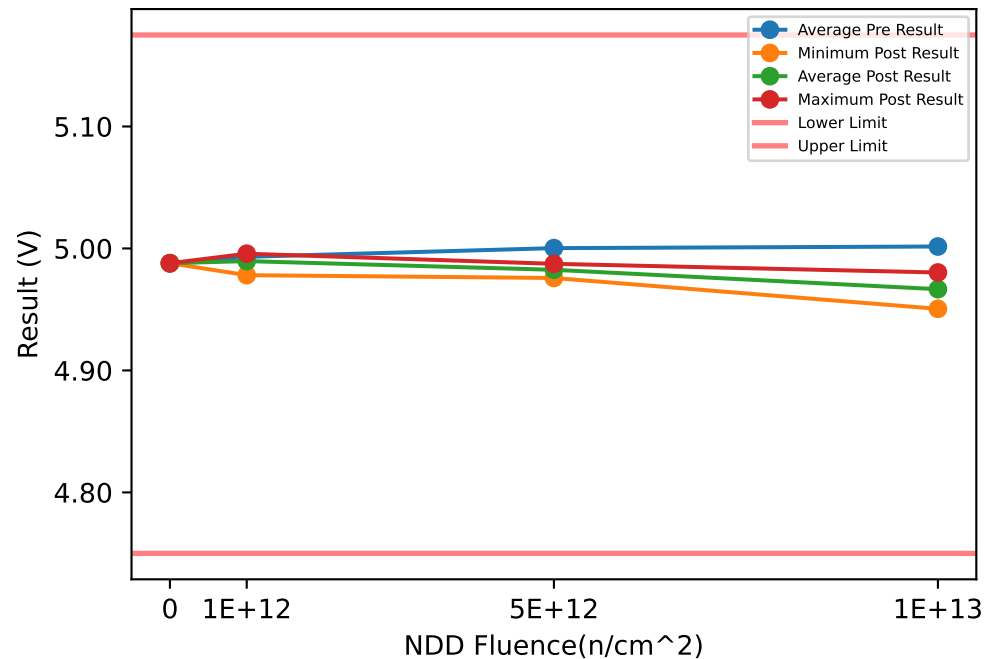


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9859	4.9859	4.9859		4.9854	4.9854	4.9854		-0.0005	-0.0005	-0.0005	
1e+12	4.9888	5.0029	5.0157	0.013502	4.9852	4.9995	5.0126	0.013739	-0.0036	-0.0034333	-0.0031	0.00028868
5e+12	4.9952	5.0073	5.0213	0.013161	4.9777	4.9907	5.005	0.013696	-0.0175	-0.016567	-0.0159	0.00083267
1e+13	4.9976	5.008	5.0158	0.0093607	4.9627	4.973	4.9826	0.0099721	-0.0367	-0.034933	-0.0332	0.0017502

Device Test: 61.14 V_BP5H(V_BP5H IIM 500kHz VIN_12V)

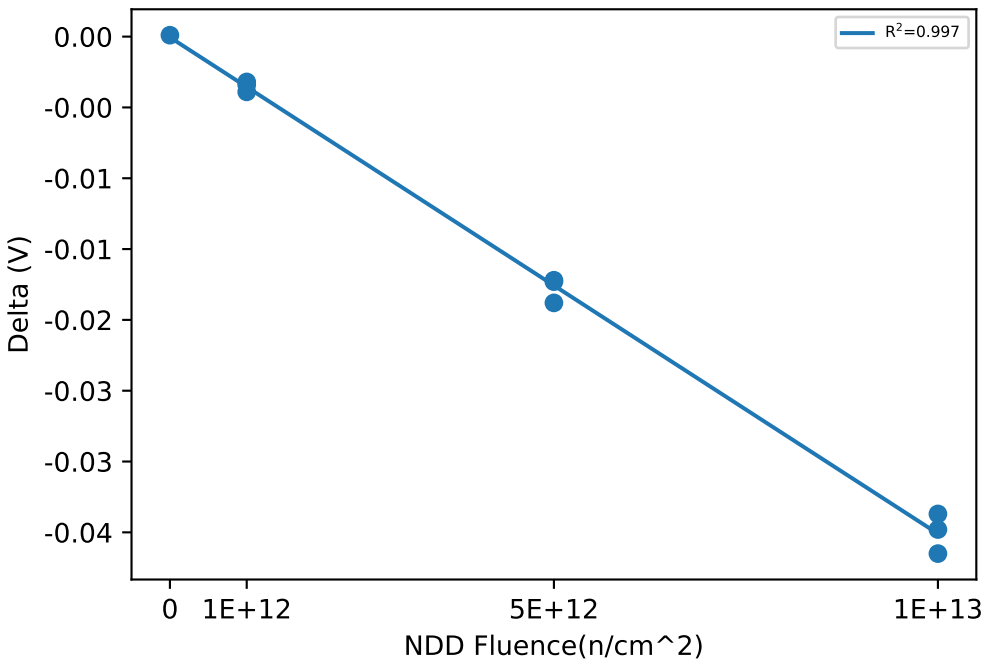
NDD vs Result Stats



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

Serial #	Fluence(n/cm ²)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.982	4.9781	-0.0039
551	1e+12	NDD	4.9983	4.9951	-0.0032
552	1e+12	NDD	4.9991	4.9957	-0.0034
553	5e+12	NDD	4.9946	4.9758	-0.0188
554	5e+12	NDD	5.0047	4.9874	-0.0173
555	5e+12	NDD	5.0015	4.9843	-0.0172
556	1e+13	NDD	4.9842	4.9505	-0.0337
557	1e+13	NDD	5.0168	4.9803	-0.0365
558	1e+13	NDD	5.0038	4.969	-0.0348
559	0	NDD, Ctrl	4.9878	4.9879	0.0001

NDD vs Post - Pre Exposure Delta

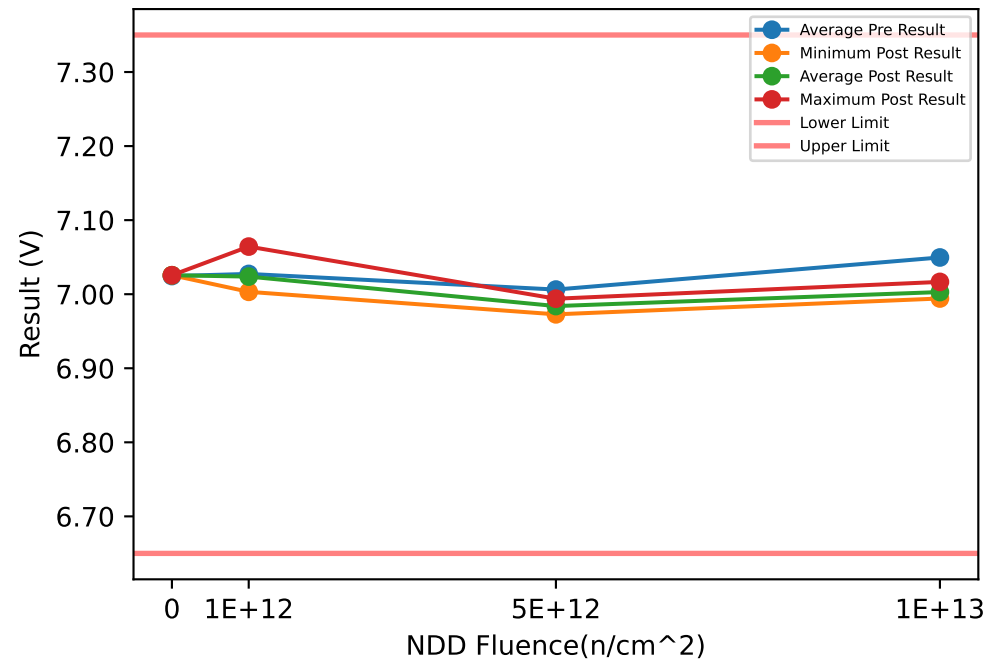


Test Statistics (V)

Fluence(n/cm ²)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9878	4.9878	4.9878		4.9879	4.9879	4.9879		0.0001	0.0001	0.0001	
1e+12	4.982	4.9931	4.9991	0.00965	4.9781	4.9896	4.9957	0.0099927	-0.0039	-0.0035	-0.0032	0.00036056
5e+12	4.9946	5.0003	5.0047	0.0051617	4.9758	4.9825	4.9874	0.0060058	-0.0188	-0.017767	-0.0172	0.00089629
1e+13	4.9842	5.0016	5.0168	0.016411	4.9505	4.9666	4.9803	0.015044	-0.0365	-0.035	-0.0337	0.0014107

Device Test: 61.15 V_BP7L(V_BP7L IIM 1MHz VIN_12V)

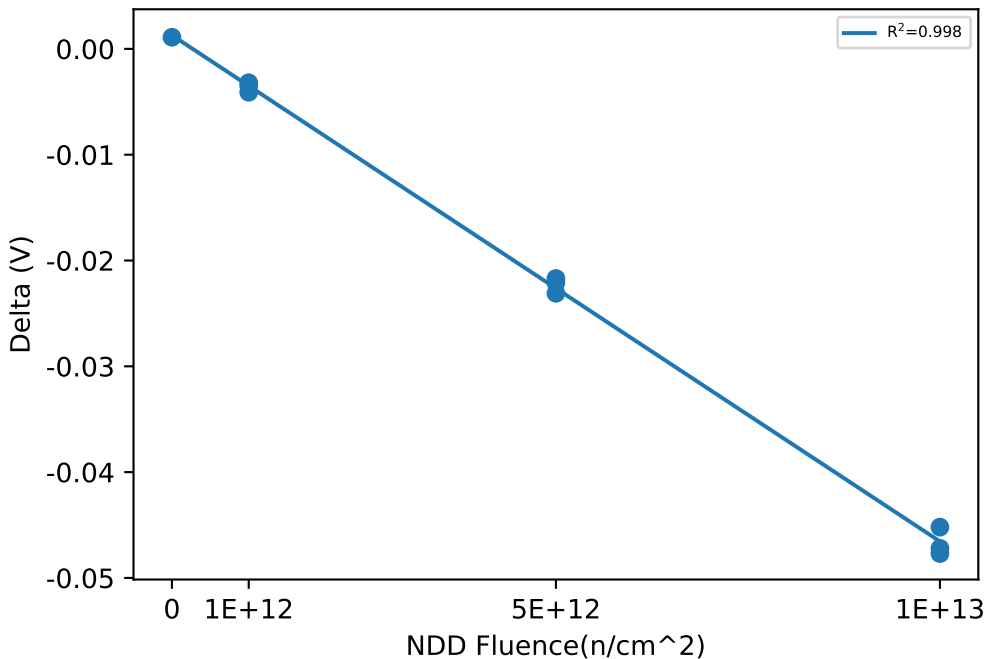
NDD vs Result Stats



Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	7.0064	7.0032	-0.0032
551	1e+12	NDD	7.0073	7.0038	-0.0035
552	1e+12	NDD	7.0684	7.0643	-0.0041
553	5e+12	NDD	7.0156	6.9939	-0.0217
554	5e+12	NDD	7.0083	6.9852	-0.0231
555	5e+12	NDD	6.9949	6.9728	-0.0221
556	1e+13	NDD	7.0394	6.9942	-0.0452
557	1e+13	NDD	7.0638	7.0166	-0.0472
558	1e+13	NDD	7.0456	6.9979	-0.0477
559	0	NDD, Ctrl	7.0245	7.0256	0.0011

NDD vs Post - Pre Exposure Delta

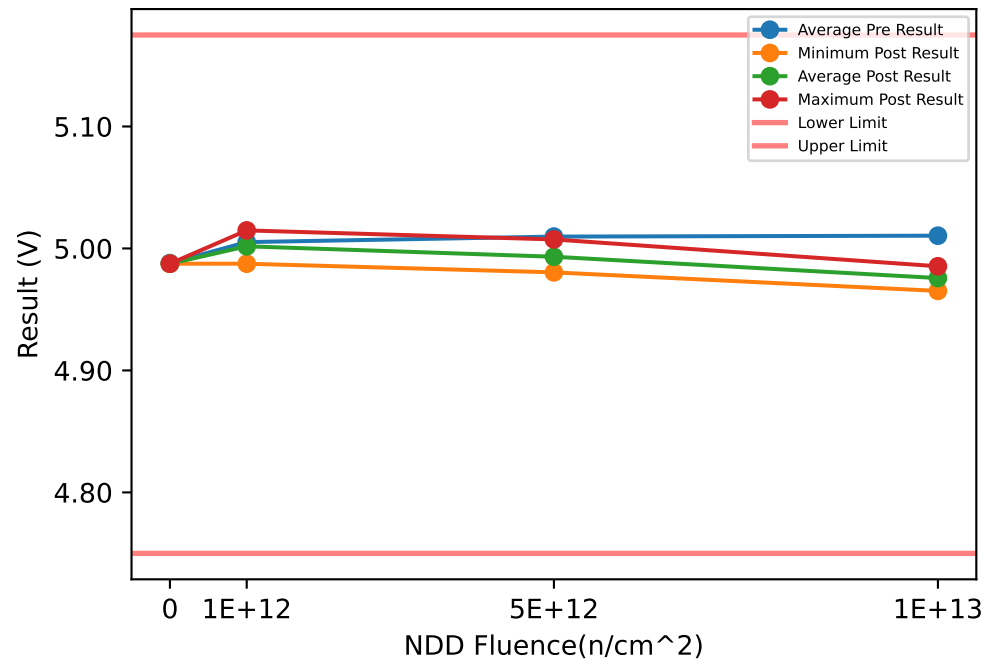


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0245	7.0245	7.0245		7.0256	7.0256	7.0256		0.0011	0.0011	0.0011	
1e+12	7.0064	7.0274	7.0684	0.035539	7.0032	7.0238	7.0643	0.035104	-0.0041	-0.0036	-0.0032	0.00045826
5e+12	6.9949	7.0063	7.0156	0.010499	6.9728	6.984	6.9939	0.010604	-0.0231	-0.0223	-0.0217	0.00072111
1e+13	7.0394	7.0496	7.0638	0.012682	6.9942	7.0029	7.0166	0.012008	-0.0477	-0.0467	-0.0452	0.0013229

Device Test: 61.16 V_BP5L(V_BP5L IIM 1MHz VIN_12V)

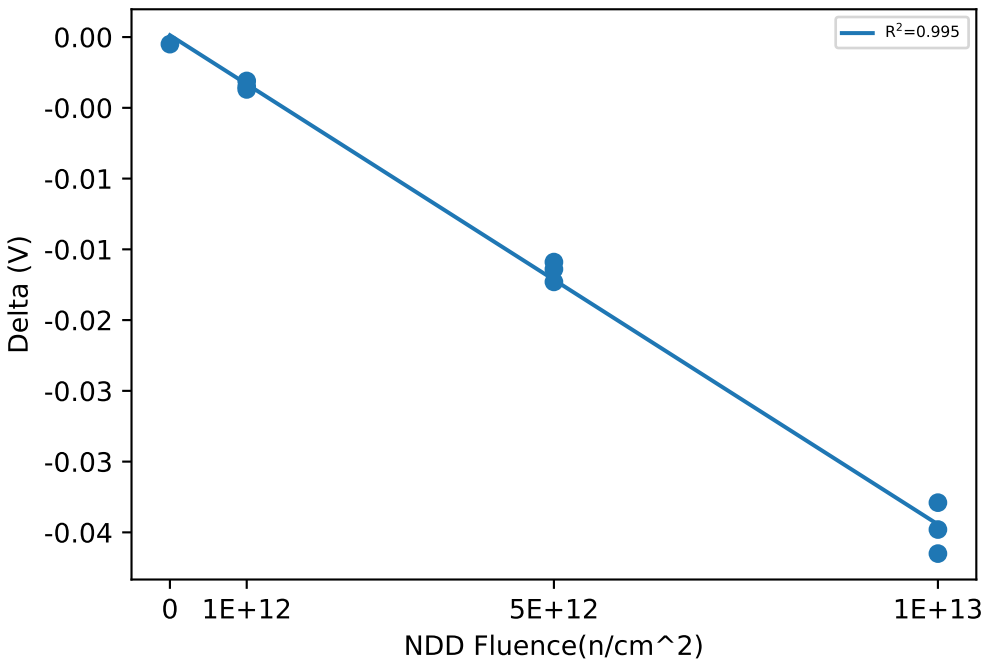
NDD vs Result Stats



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

Serial #	Fluence(n/cm ²)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.991	4.9875	-0.0035
551	1e+12	NDD	5.0067	5.003	-0.0037
552	1e+12	NDD	5.0179	5.0148	-0.0031
553	5e+12	NDD	5.0077	4.9918	-0.0159
554	5e+12	NDD	4.9977	4.9804	-0.0173
555	5e+12	NDD	5.0238	5.0074	-0.0164
556	1e+13	NDD	5	4.9652	-0.0348
557	1e+13	NDD	5.0183	4.9854	-0.0329
558	1e+13	NDD	5.0131	4.9766	-0.0365
559	0	NDD, Ctrl	4.988	4.9875	-0.0005

NDD vs Post - Pre Exposure Delta

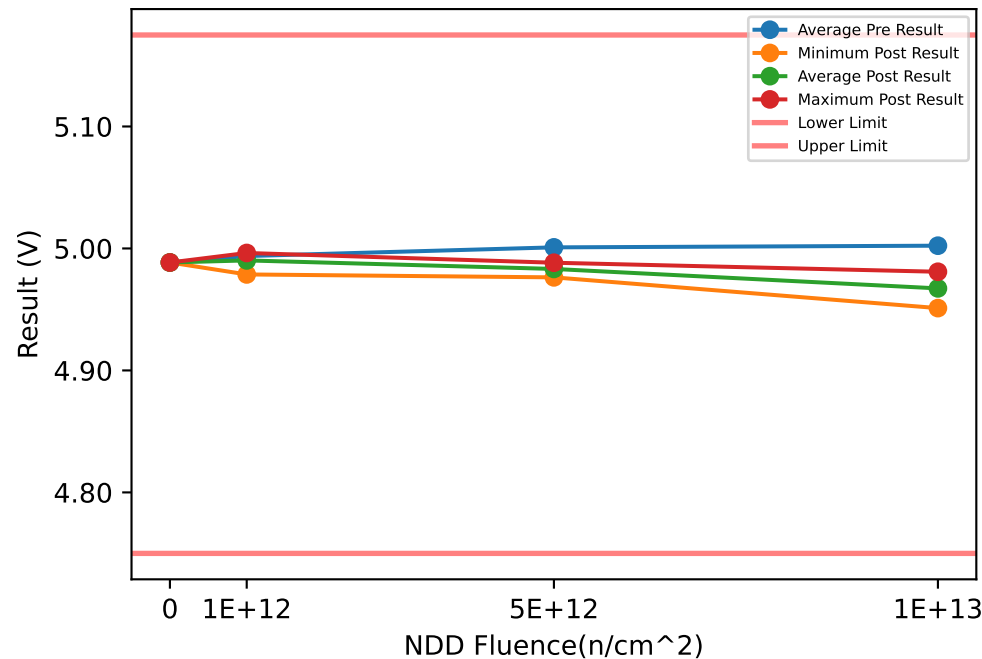


Test Statistics (V)

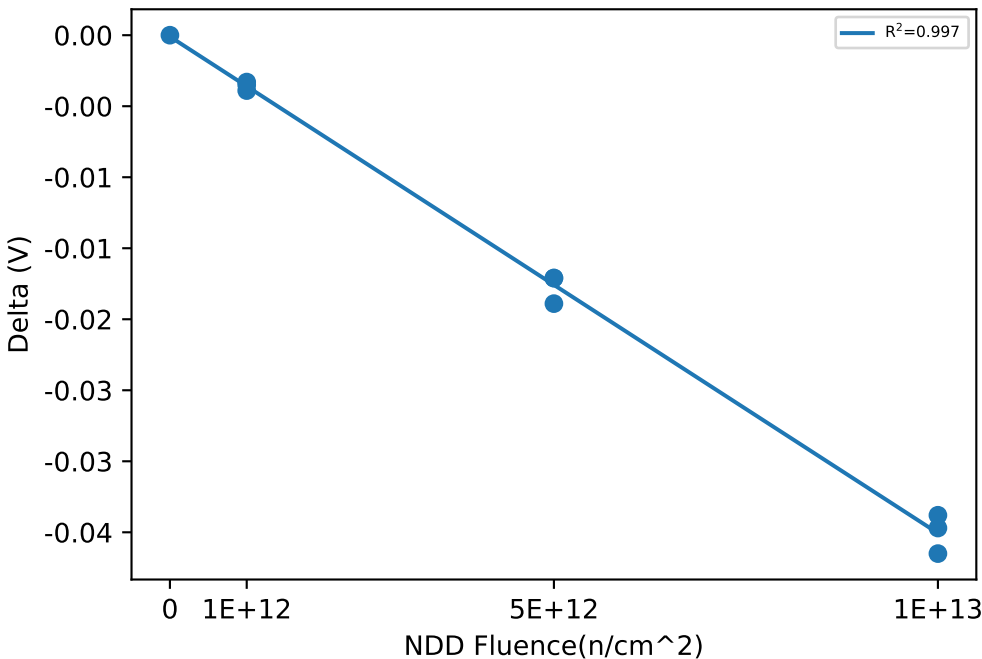
Fluence(n/cm ²)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.988	4.988	4.988		4.9875	4.9875	4.9875		-0.0005	-0.0005	-0.0005	
1e+12	4.991	5.0052	5.0179	0.013513	4.9875	5.0018	5.0148	0.013692	-0.0037	-0.0034333	-0.0031	0.00030551
5e+12	4.9977	5.0097	5.0238	0.013168	4.9804	4.9932	5.0074	0.013554	-0.0173	-0.016533	-0.0159	0.00070946
1e+13	5	5.0105	5.0183	0.0094299	4.9652	4.9757	4.9854	0.010128	-0.0365	-0.034733	-0.0329	0.0018009

Device Test: 61.17 V_BP5H(V_BP5H IIM 1MHz VIN_12V)

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

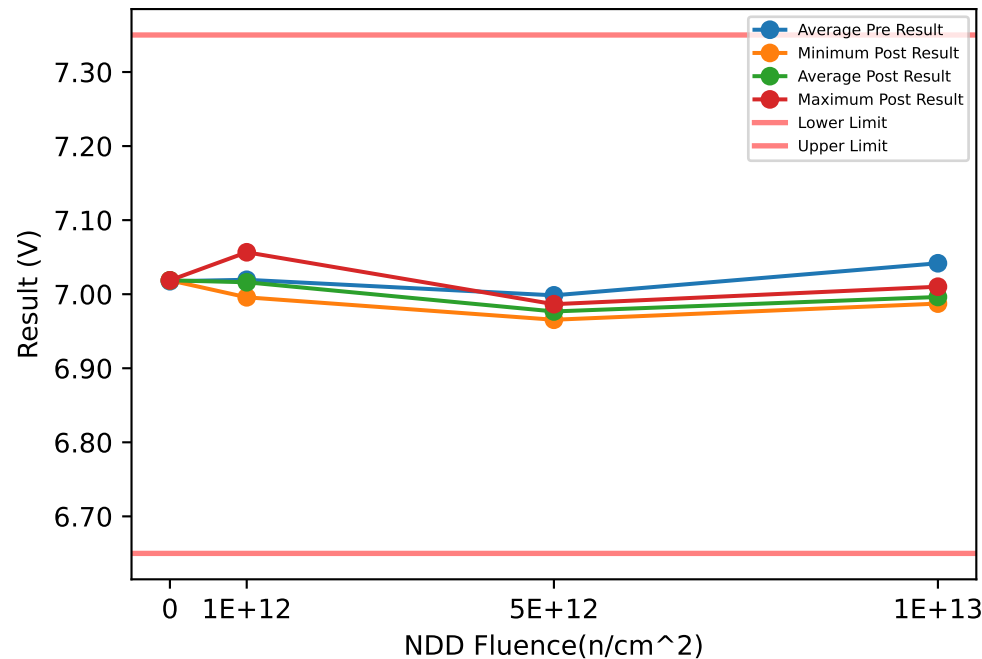
Serial #	Fluence(n/cm ²)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.9826	4.9787	-0.0039
551	1e+12	NDD	4.9989	4.9956	-0.0033
552	1e+12	NDD	4.9998	4.9963	-0.0035
553	5e+12	NDD	4.9952	4.9763	-0.0189
554	5e+12	NDD	5.0054	4.9883	-0.0171
555	5e+12	NDD	5.0021	4.985	-0.0171
556	1e+13	NDD	4.9849	4.9511	-0.0338
557	1e+13	NDD	5.0174	4.9809	-0.0365
558	1e+13	NDD	5.0045	4.9698	-0.0347
559	0	NDD, Ctrl	4.9885	4.9885	0

Test Statistics (V)

Fluence(n/cm ²)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9885	4.9885	4.9885		4.9885	4.9885	4.9885		0	0	0	
1e+12	4.9826	4.9938	4.9998	0.0096811	4.9787	4.9902	4.9963	0.0099654	-0.0039	-0.0035667	-0.0033	0.00030551
5e+12	4.9952	5.0009	5.0054	0.0052048	4.9763	4.9832	4.9883	0.0061992	-0.0189	-0.0177	-0.0171	0.0010392
1e+13	4.9849	5.0023	5.0174	0.016365	4.9511	4.9673	4.9809	0.015061	-0.0365	-0.035	-0.0338	0.0013748

Device Test: 61.18 V_BP7L(V_BP7L IIM 2MHz VIN_12V)

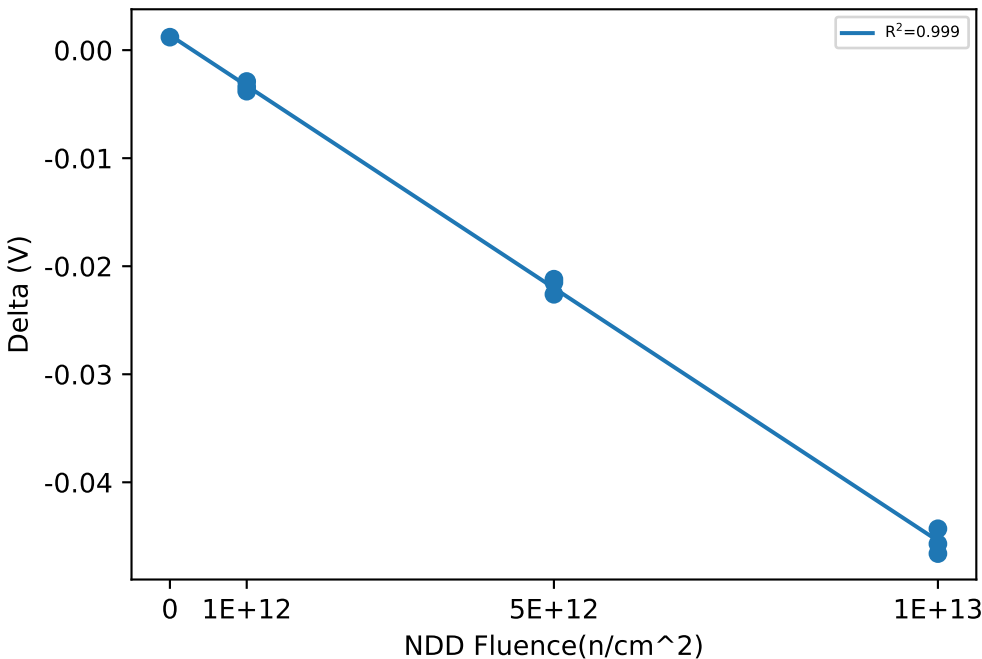
NDD vs Result Stats



Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	6.9987	6.9958	-0.0029
551	1e+12	NDD	6.9993	6.9959	-0.0034
552	1e+12	NDD	7.0604	7.0566	-0.0038
553	5e+12	NDD	7.0077	6.9865	-0.0212
554	5e+12	NDD	7.0007	6.9781	-0.0226
555	5e+12	NDD	6.987	6.9655	-0.0215
556	1e+13	NDD	7.0316	6.9873	-0.0443
557	1e+13	NDD	7.0558	7.0101	-0.0457
558	1e+13	NDD	7.0379	6.9913	-0.0466
559	0	NDD, Ctrl	7.0175	7.0187	0.0012

NDD vs Post - Pre Exposure Delta

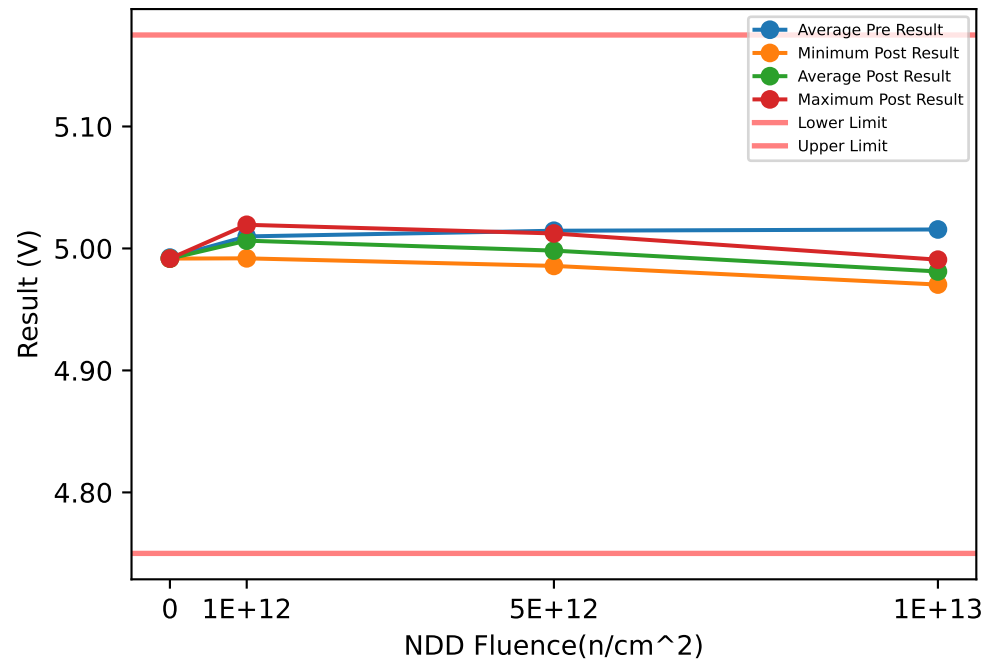


Test Statistics (V)

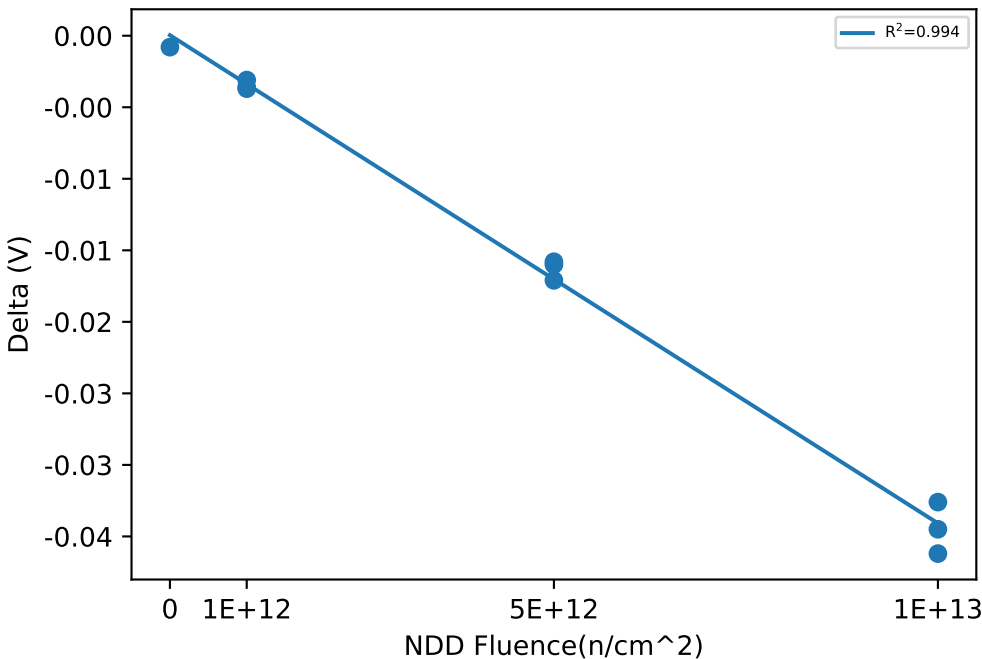
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0175	7.0175	7.0175		7.0187	7.0187	7.0187		0.0012	0.0012	0.0012	
1e+12	6.9987	7.0195	7.0604	0.035451	6.9958	7.0161	7.0566	0.035074	-0.0038	-0.0033667	-0.0029	0.00045092
5e+12	6.987	6.9985	7.0077	0.010529	6.9655	6.9767	6.9865	0.01057	-0.0226	-0.021767	-0.0212	0.00073711
1e+13	7.0316	7.0418	7.0558	0.012555	6.9873	6.9962	7.0101	0.012174	-0.0466	-0.045533	-0.0443	0.001159

Device Test: 61.19 V_BP5L(V_BP5L IIM 2MHz VIN_12V)

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

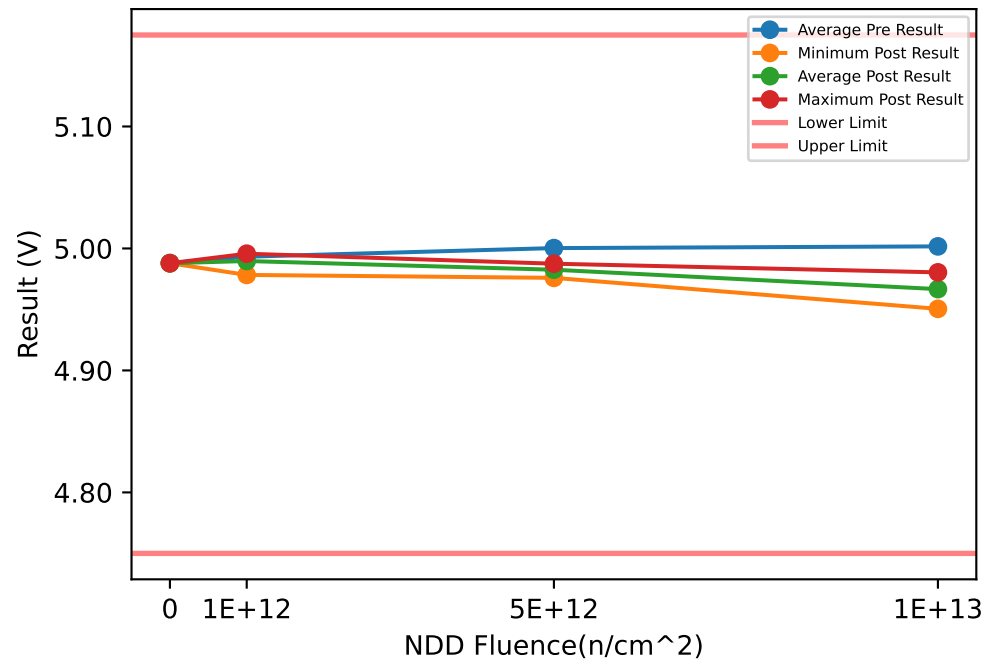
Serial #	Fluence(n/cm ²)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.9955	4.9919	-0.0036
551	1e+12	NDD	5.0116	5.0079	-0.0037
552	1e+12	NDD	5.0225	5.0194	-0.0031
553	5e+12	NDD	5.0125	4.9967	-0.0158
554	5e+12	NDD	5.0028	4.9857	-0.0171
555	5e+12	NDD	5.0283	5.0123	-0.016
556	1e+13	NDD	5.0049	4.9704	-0.0345
557	1e+13	NDD	5.0234	4.9908	-0.0326
558	1e+13	NDD	5.0184	4.9822	-0.0362
559	0	NDD, Ctrl	4.9925	4.9917	-0.0008

Test Statistics (V)

Fluence(n/cm ²)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9925	4.9925	4.9925		4.9917	4.9917	4.9917		-0.0008	-0.0008	-0.0008	
1e+12	4.9955	5.0099	5.0225	0.013583	4.9919	5.0064	5.0194	0.013811	-0.0037	-0.0034667	-0.0031	0.00032146
5e+12	5.0028	5.0145	5.0283	0.012871	4.9857	4.9982	5.0123	0.013366	-0.0171	-0.0163	-0.0158	0.0007
1e+13	5.0049	5.0156	5.0234	0.0095699	4.9704	4.9811	4.9908	0.010242	-0.0362	-0.034433	-0.0326	0.0018009

Device Test: 61.2 V_BP5H(V_BP5H PWM 500kHz VIN_12V)

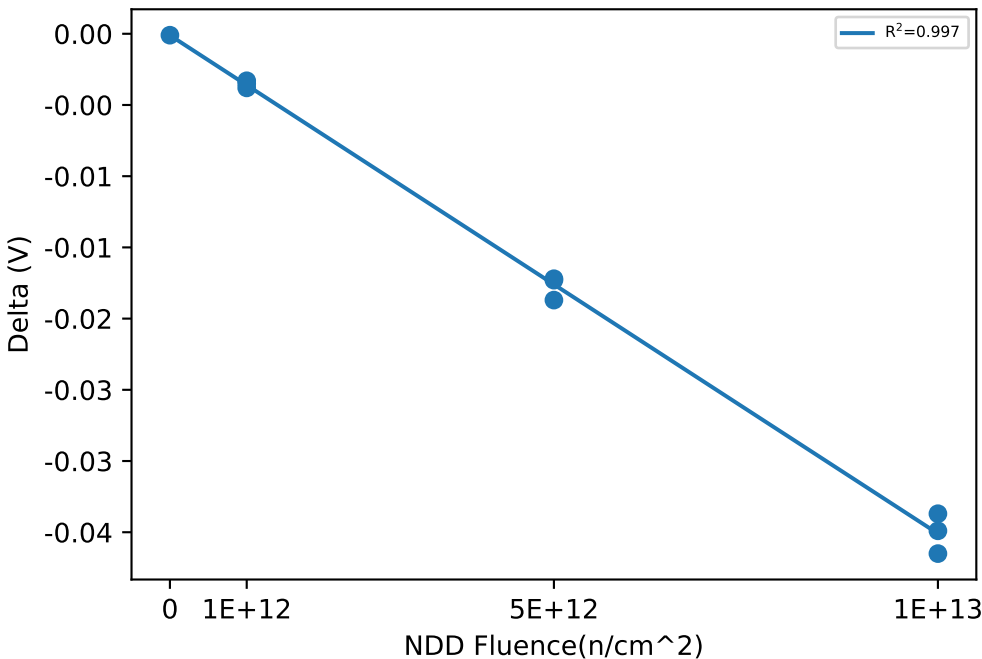
NDD vs Result Stats



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

Serial #	Fluence(n/cm ²)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.9821	4.9783	-0.0038
551	1e+12	NDD	4.9984	4.9951	-0.0033
552	1e+12	NDD	4.9992	4.9957	-0.0035
553	5e+12	NDD	4.9946	4.9759	-0.0187
554	5e+12	NDD	5.0048	4.9875	-0.0173
555	5e+12	NDD	5.0015	4.9843	-0.0172
556	1e+13	NDD	4.9842	4.9505	-0.0337
557	1e+13	NDD	5.0169	4.9804	-0.0365
558	1e+13	NDD	5.004	4.9691	-0.0349
559	0	NDD, Ctrl	4.988	4.9879	-0.0001

NDD vs Post - Pre Exposure Delta

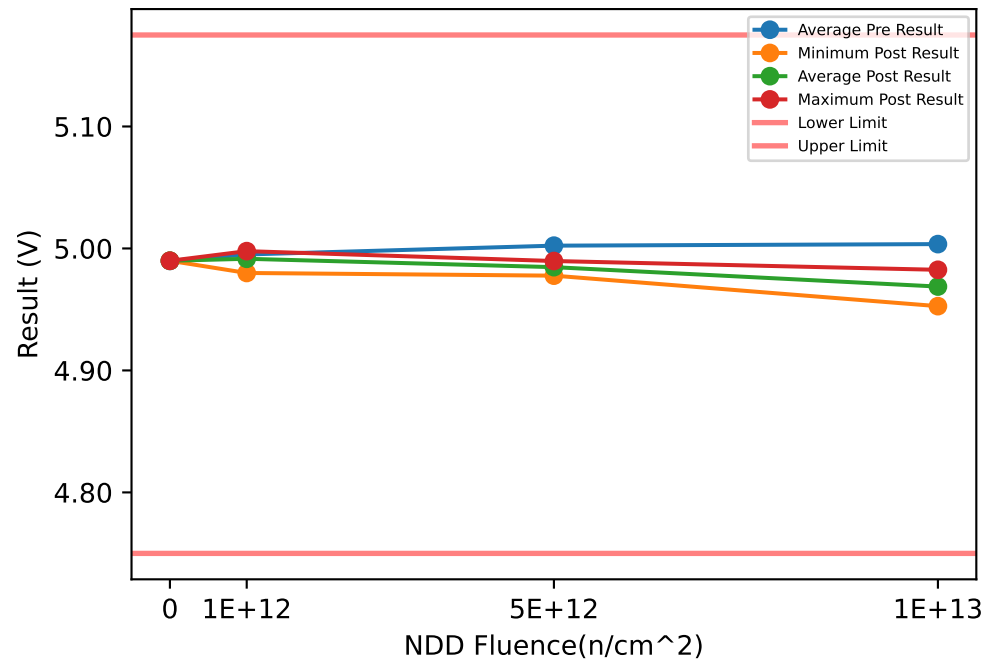


Test Statistics (V)

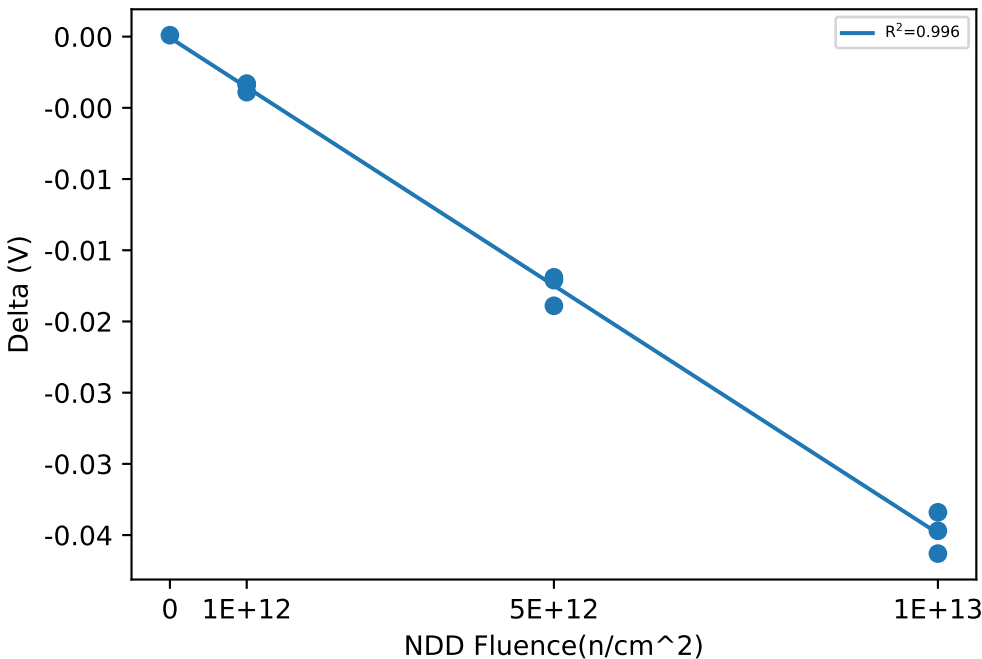
Fluence(n/cm ²)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.988	4.988	4.988		4.9879	4.9879	4.9879		-0.0001	-0.0001	-0.0001	
1e+12	4.9821	4.9932	4.9992	0.00965	4.9783	4.9897	4.9957	0.0098772	-0.0038	-0.0035333	-0.0033	0.00025166
5e+12	4.9946	5.0003	5.0048	0.0052048	4.9759	4.9826	4.9875	0.0059911	-0.0187	-0.017733	-0.0172	0.00083865
1e+13	4.9842	5.0017	5.0169	0.016471	4.9505	4.9667	4.9804	0.015098	-0.0365	-0.035033	-0.0337	0.0014048

Device Test: 61.20 V_BP5H(V_BP5H IIM 2MHz VIN_12V)

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

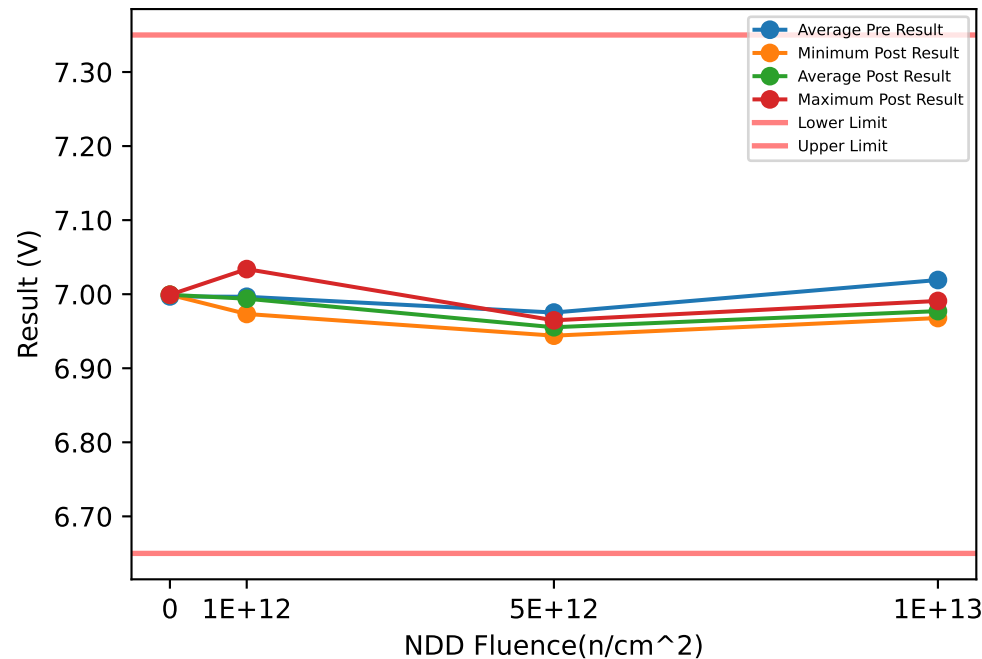
Serial #	Fluence(n/cm ²)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.9838	4.9799	-0.0039
551	1e+12	NDD	5.0003	4.9969	-0.0034
552	1e+12	NDD	5.0011	4.9978	-0.0033
553	5e+12	NDD	4.9966	4.9777	-0.0189
554	5e+12	NDD	5.0068	4.9897	-0.0171
555	5e+12	NDD	5.0035	4.9866	-0.0169
556	1e+13	NDD	4.9861	4.9527	-0.0334
557	1e+13	NDD	5.0188	4.9825	-0.0363
558	1e+13	NDD	5.0058	4.9711	-0.0347
559	0	NDD, Ctrl	4.9898	4.9899	0.0001

Test Statistics (V)

Fluence(n/cm ²)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9898	4.9898	4.9898		4.9899	4.9899	4.9899		0.0001	0.0001	0.0001	
1e+12	4.9838	4.9951	5.0011	0.0097654	4.9799	4.9915	4.9978	0.010085	-0.0039	-0.0035333	-0.0033	0.00032146
5e+12	4.9966	5.0023	5.0068	0.0052048	4.9777	4.9847	4.9897	0.0062292	-0.0189	-0.017633	-0.0169	0.0011015
1e+13	4.9861	5.0036	5.0188	0.016464	4.9527	4.9688	4.9825	0.015036	-0.0363	-0.0348	-0.0334	0.0014526

Device Test: 61.21 V_BP7L(V_BP7L IIM 5MHz VIN_12V)

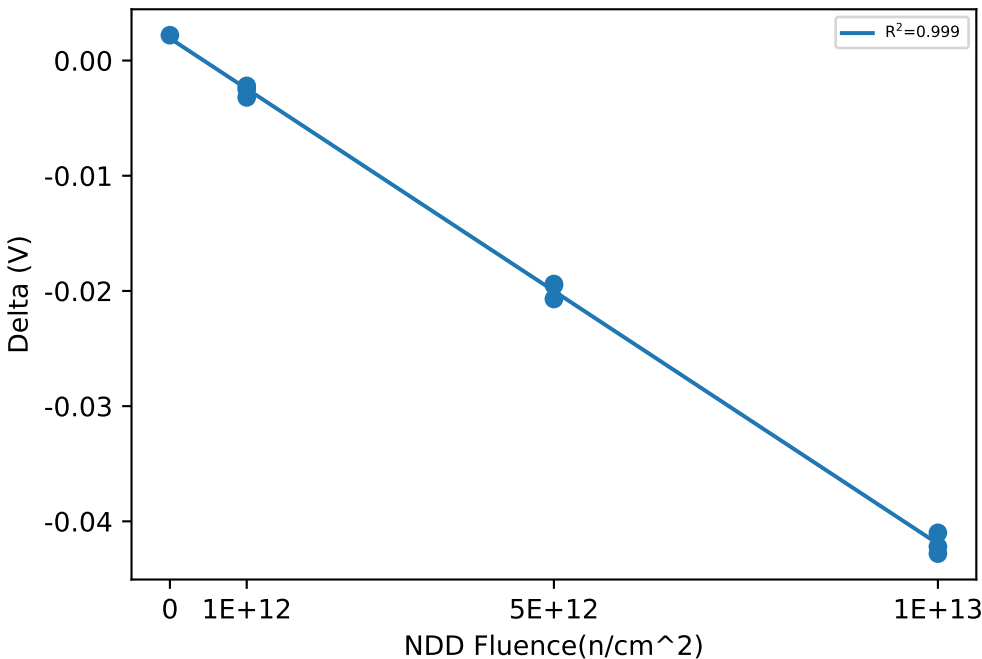
NDD vs Result Stats



Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	6.9767	6.9745	-0.0022
551	1e+12	NDD	6.9758	6.9733	-0.0025
552	1e+12	NDD	7.0371	7.0339	-0.0032
553	5e+12	NDD	6.9841	6.9647	-0.0194
554	5e+12	NDD	6.9781	6.9574	-0.0207
555	5e+12	NDD	6.9635	6.944	-0.0195
556	1e+13	NDD	7.0088	6.9678	-0.041
557	1e+13	NDD	7.0331	6.9909	-0.0422
558	1e+13	NDD	7.0156	6.9728	-0.0428
559	0	NDD, Ctrl	6.997	6.9992	0.0022

NDD vs Post - Pre Exposure Delta

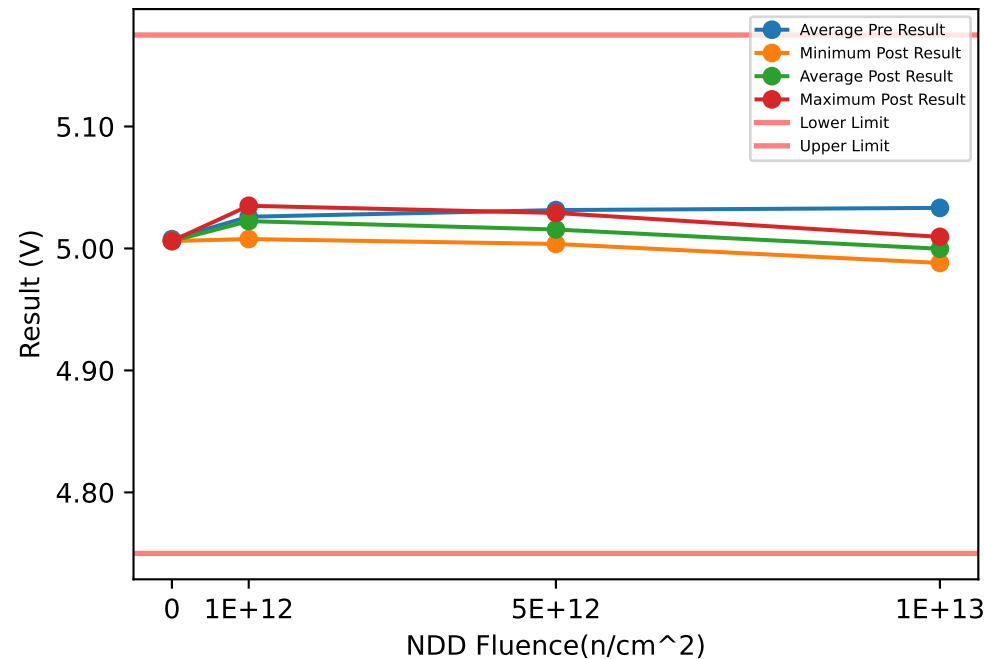


Test Statistics (V)

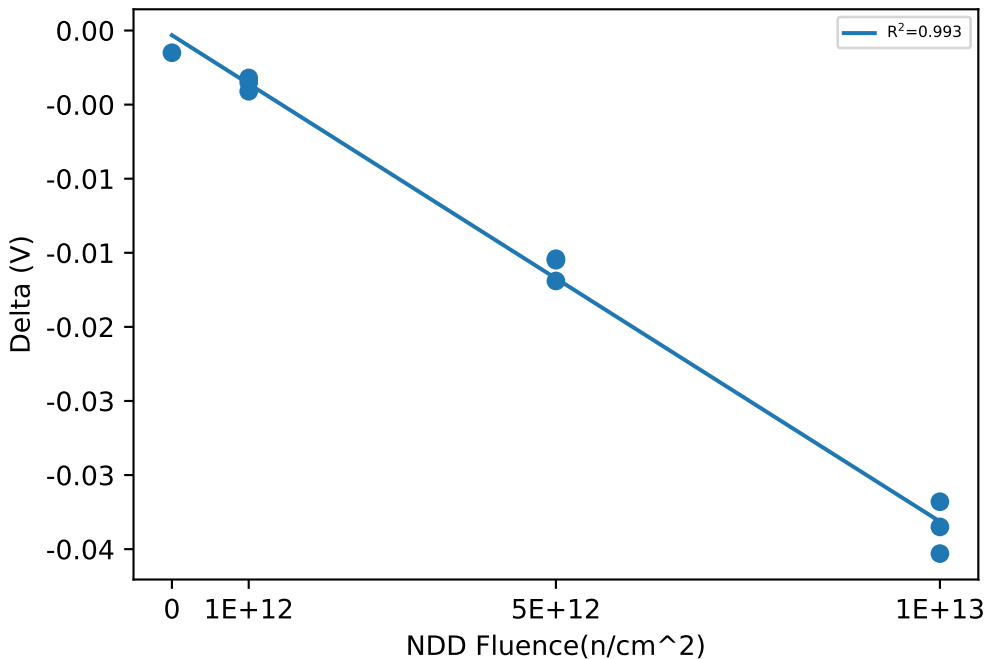
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.997	6.997	6.997		6.9992	6.9992	6.9992		0.0022	0.0022	0.0022	
1e+12	6.9758	6.9965	7.0371	0.035135	6.9733	6.9939	7.0339	0.034646	-0.0032	-0.0026333	-0.0022	0.00051316
5e+12	6.9635	6.9752	6.9841	0.010595	6.944	6.9554	6.9647	0.010499	-0.0207	-0.019867	-0.0194	0.00072342
1e+13	7.0088	7.0192	7.0331	0.012536	6.9678	6.9772	6.9909	0.012153	-0.0428	-0.042	-0.041	0.00091652

Device Test: 61.22 V_BP5L(V_BP5L IIM 5MHz VIN_12V)

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

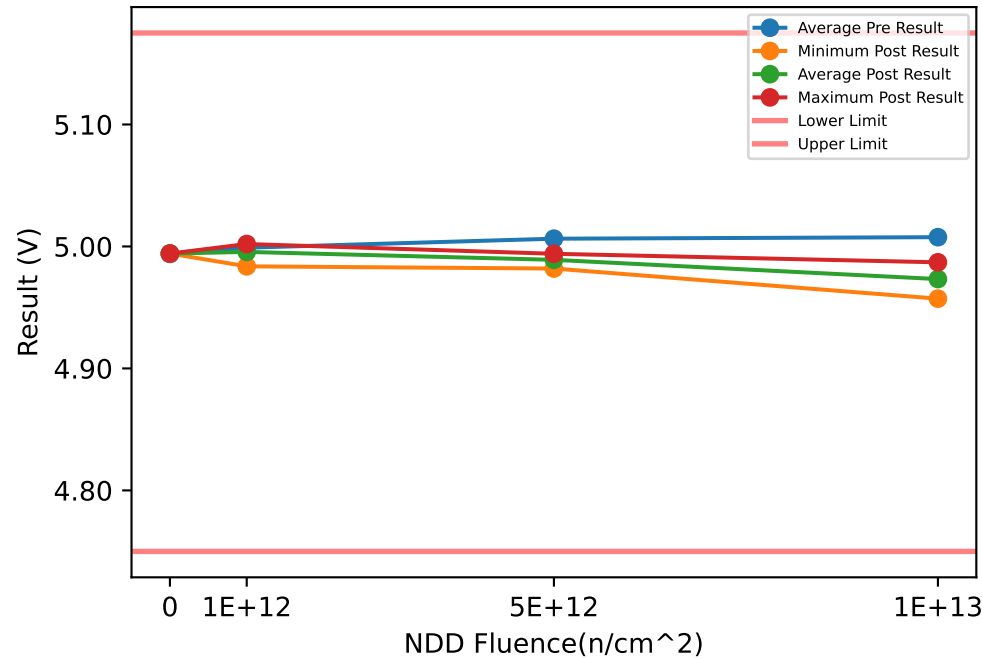
Serial #	Fluence(n/cm ²)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	5.0112	5.0077	-0.0035
551	1e+12	NDD	5.0286	5.0245	-0.0041
552	1e+12	NDD	5.0382	5.035	-0.0032
553	5e+12	NDD	5.0293	5.0138	-0.0155
554	5e+12	NDD	5.0206	5.0037	-0.0169
555	5e+12	NDD	5.0445	5.0291	-0.0154
556	1e+13	NDD	5.0216	4.9881	-0.0335
557	1e+13	NDD	5.0413	5.0095	-0.0318
558	1e+13	NDD	5.0369	5.0016	-0.0353
559	0	NDD, Ctrl	5.0076	5.0061	-0.0015

Test Statistics (V)

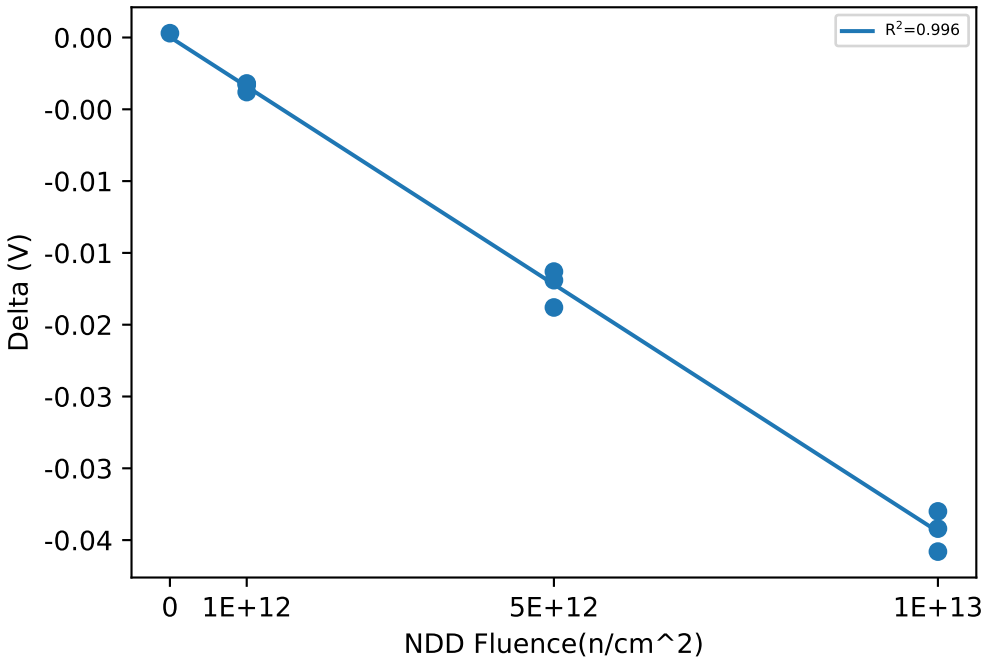
Fluence(n/cm ²)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0076	5.0076	5.0076		5.0061	5.0061	5.0061		-0.0015	-0.0015	-0.0015	
1e+12	5.0112	5.026	5.0382	0.013686	5.0077	5.0224	5.035	0.013771	-0.0041	-0.0036	-0.0032	0.00045826
5e+12	5.0206	5.0315	5.0445	0.012096	5.0037	5.0155	5.0291	0.012788	-0.0169	-0.015933	-0.0154	0.00083865
1e+13	5.0216	5.0333	5.0413	0.01034	4.9881	4.9997	5.0095	0.010821	-0.0353	-0.033533	-0.0318	0.0017502

Device Test: 61.23 V_BP5H(V_BP5H IIM 5MHz VIN_12V)

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

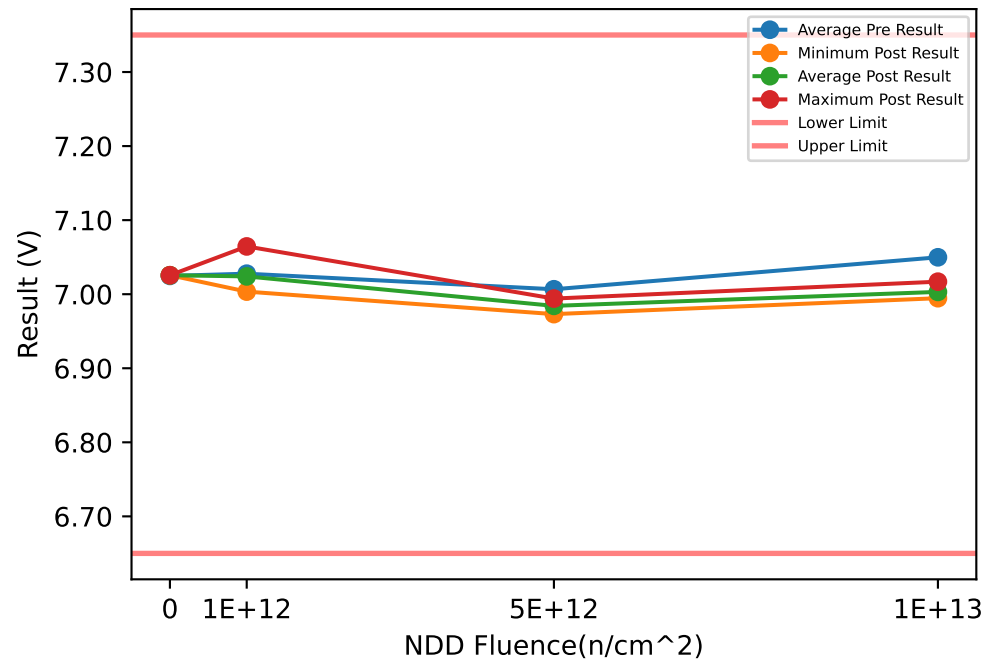
Serial #	Fluence(n/cm ²)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.9875	4.9837	-0.0038
551	1e+12	NDD	5.0042	5.0009	-0.0033
552	1e+12	NDD	5.0052	5.002	-0.0032
553	5e+12	NDD	5.0007	4.9819	-0.0188
554	5e+12	NDD	5.0109	4.994	-0.0169
555	5e+12	NDD	5.0075	4.9912	-0.0163
556	1e+13	NDD	4.9902	4.9572	-0.033
557	1e+13	NDD	5.0228	4.987	-0.0358
558	1e+13	NDD	5.0098	4.9756	-0.0342
559	0	NDD, Ctrl	4.9939	4.9942	0.0003

Test Statistics (V)

Fluence(n/cm ²)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9939	4.9939	4.9939		4.9942	4.9942	4.9942		0.0003	0.0003	0.0003	
1e+12	4.9875	4.999	5.0052	0.009943	4.9837	4.9955	5.002	0.010263	-0.0038	-0.0034333	-0.0032	0.00032146
5e+12	5.0007	5.0064	5.0109	0.0051936	4.9819	4.989	4.994	0.0063343	-0.0188	-0.017333	-0.0163	0.0013051
1e+13	4.9902	5.0076	5.0228	0.016411	4.9572	4.9733	4.987	0.015036	-0.0358	-0.034333	-0.033	0.0014048

Device Test: 61.3 V_BP7L(V_BP7L PWM 1MHz VIN_12V)

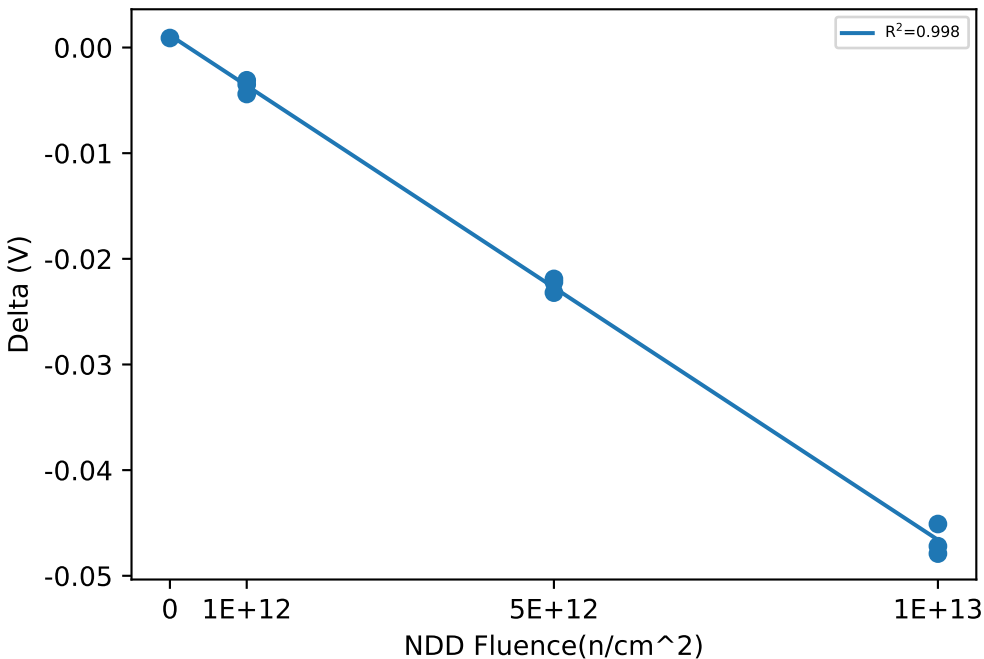
NDD vs Result Stats



Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	7.0066	7.0035	-0.0031
551	1e+12	NDD	7.0076	7.0041	-0.0035
552	1e+12	NDD	7.0689	7.0645	-0.0044
553	5e+12	NDD	7.016	6.9941	-0.0219
554	5e+12	NDD	7.0087	6.9855	-0.0232
555	5e+12	NDD	6.9953	6.9731	-0.0222
556	1e+13	NDD	7.0397	6.9946	-0.0451
557	1e+13	NDD	7.0641	7.0169	-0.0472
558	1e+13	NDD	7.0457	6.9978	-0.0479
559	0	NDD, Ctrl	7.0247	7.0256	0.0009

NDD vs Post - Pre Exposure Delta

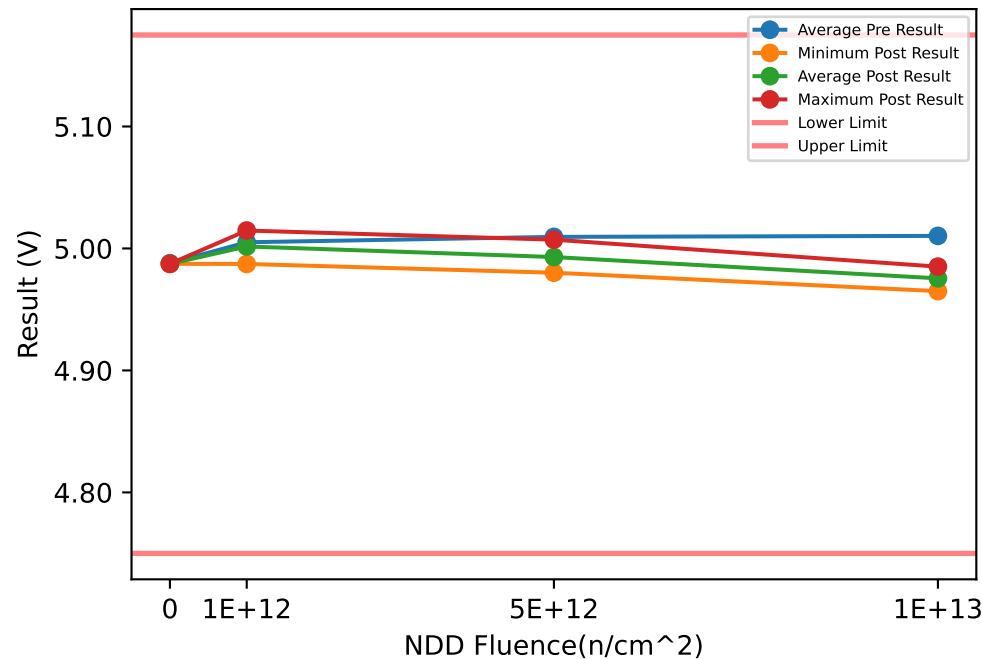


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0247	7.0247	7.0247		7.0256	7.0256	7.0256		0.0009	0.0009	0.0009	
1e+12	7.0066	7.0277	7.0689	0.035684	7.0035	7.024	7.0645	0.035046	-0.0044	-0.0036667	-0.0031	0.00066583
5e+12	6.9953	7.0067	7.016	0.010499	6.9731	6.9842	6.9941	0.010557	-0.0232	-0.022433	-0.0219	0.00068069
1e+13	7.0397	7.0498	7.0641	0.012714	6.9946	7.0031	7.0169	0.012058	-0.0479	-0.046733	-0.0451	0.0014572

Device Test: 61.4 V_BP5L(V_BP5L PWM 1MHz VIN_12V)

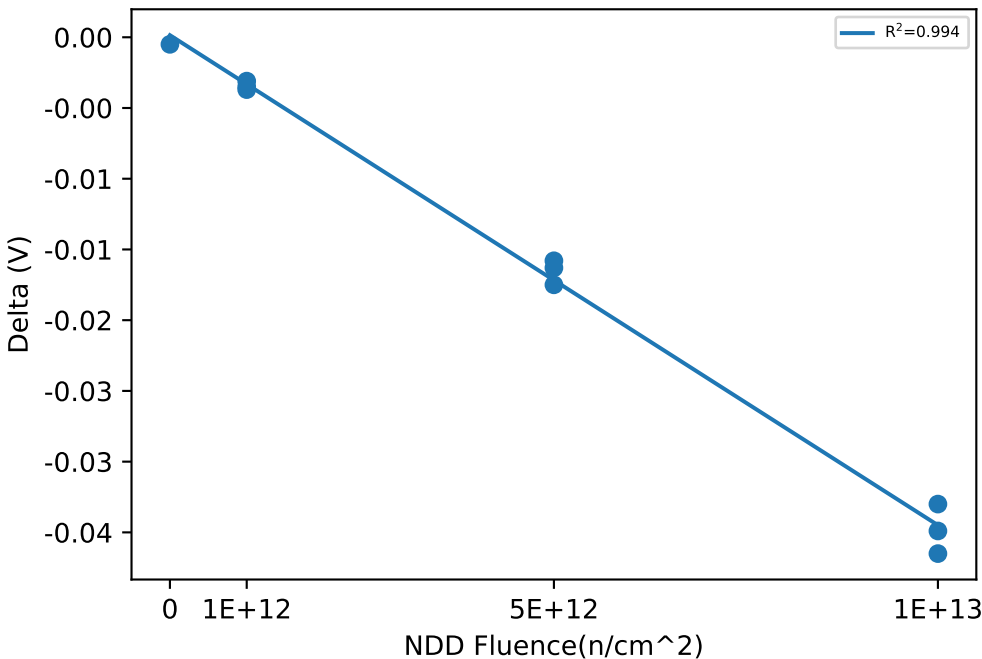
NDD vs Result Stats



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.9908	4.9873	-0.0035
551	1e+12	NDD	5.0066	5.0029	-0.0037
552	1e+12	NDD	5.0178	5.0147	-0.0031
553	5e+12	NDD	5.0074	4.9916	-0.0158
554	5e+12	NDD	4.9976	4.9801	-0.0175
555	5e+12	NDD	5.0235	5.0072	-0.0163
556	1e+13	NDD	4.9999	4.965	-0.0349
557	1e+13	NDD	5.0181	4.9851	-0.033
558	1e+13	NDD	5.0129	4.9764	-0.0365
559	0	NDD, Ctrl	4.9879	4.9874	-0.0005

NDD vs Post - Pre Exposure Delta

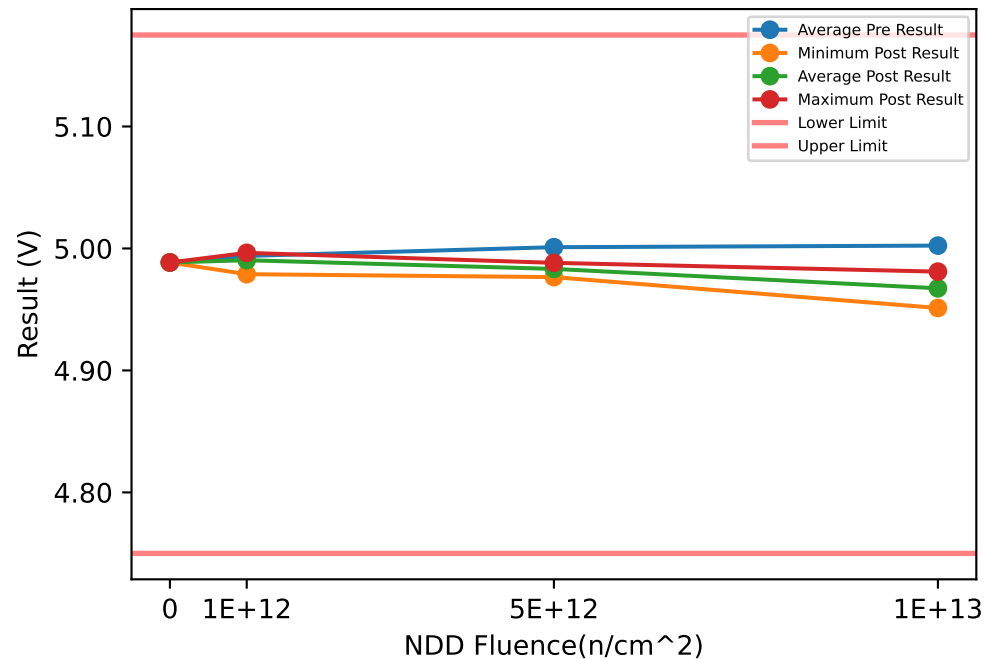


Test Statistics (V)

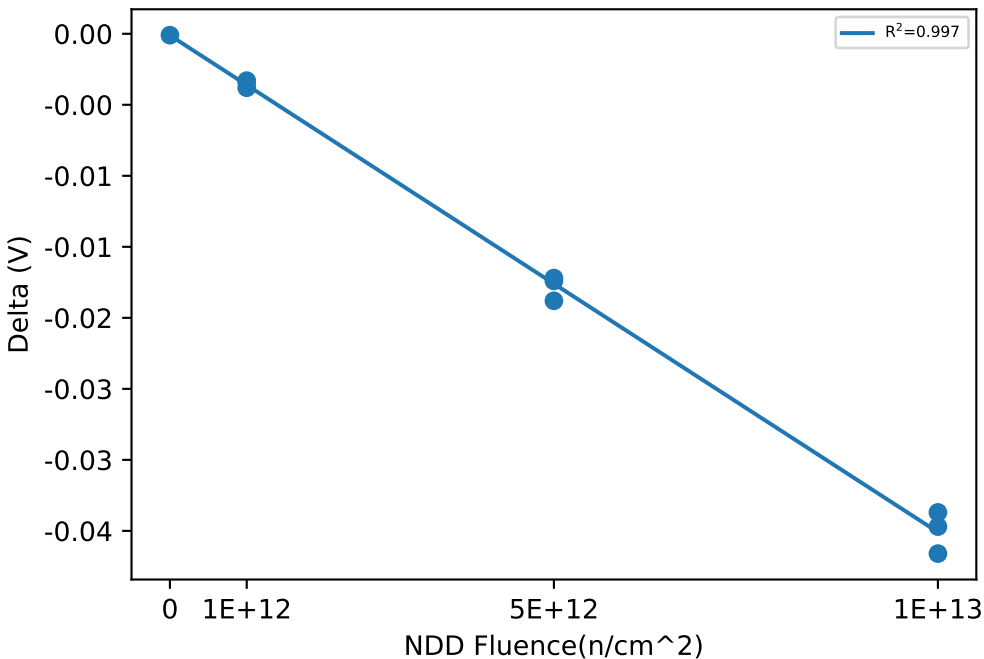
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9879	4.9879	4.9879		4.9874	4.9874	4.9874		-0.0005	-0.0005	-0.0005	
1e+12	4.9908	5.0051	5.0178	0.013565	4.9873	5.0016	5.0147	0.013744	-0.0037	-0.0034333	-0.0031	0.00030551
5e+12	4.9976	5.0095	5.0235	0.013077	4.9801	4.993	5.0072	0.013602	-0.0175	-0.016533	-0.0158	0.00087369
1e+13	4.9999	5.0103	5.0181	0.0093744	4.965	4.9755	4.9851	0.01008	-0.0365	-0.0348	-0.033	0.0017521

Device Test: 61.5 V_BP5H(V_BP5H PWM 1MHz VIN_12V)

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

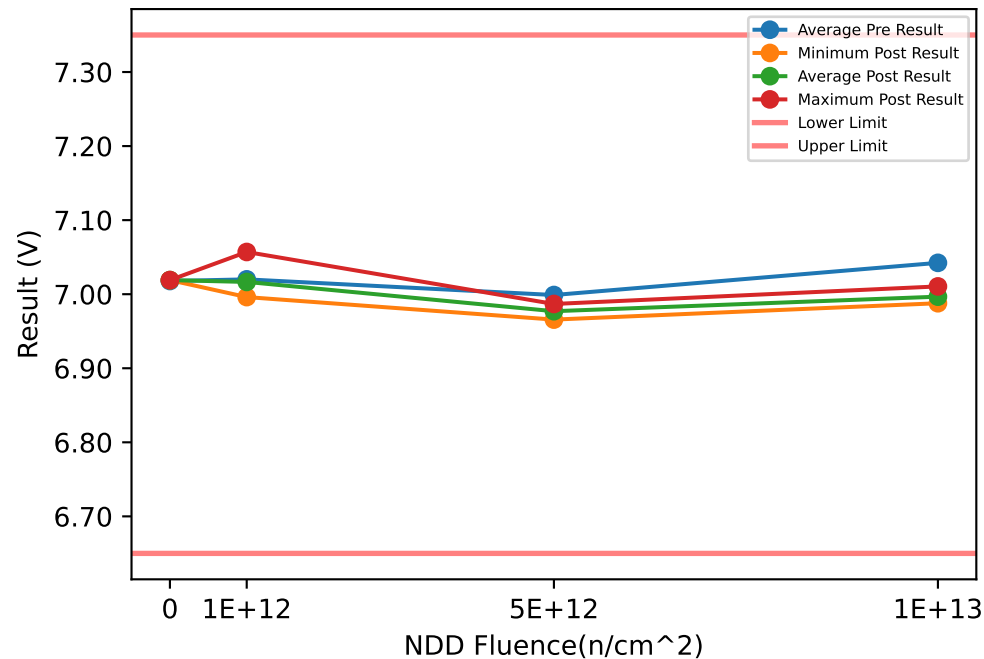
Serial #	Fluence(n/cm ²)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.9827	4.9789	-0.0038
551	1e+12	NDD	4.9991	4.9958	-0.0033
552	1e+12	NDD	4.9998	4.9964	-0.0034
553	5e+12	NDD	4.9953	4.9765	-0.0188
554	5e+12	NDD	5.0056	4.9882	-0.0174
555	5e+12	NDD	5.0022	4.985	-0.0172
556	1e+13	NDD	4.9849	4.9512	-0.0337
557	1e+13	NDD	5.0176	4.981	-0.0366
558	1e+13	NDD	5.0045	4.9698	-0.0347
559	0	NDD, Ctrl	4.9886	4.9885	-0.0001

Test Statistics (V)

Fluence(n/cm ²)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9886	4.9886	4.9886		4.9885	4.9885	4.9885		-0.0001	-0.0001	-0.0001	
1e+12	4.9827	4.9939	4.9998	0.0096769	4.9789	4.9904	4.9964	0.009935	-0.0038	-0.0035	-0.0033	0.00026458
5e+12	4.9953	5.001	5.0056	0.0052482	4.9765	4.9832	4.9882	0.0060468	-0.0188	-0.0178	-0.0172	0.00087178
1e+13	4.9849	5.0023	5.0176	0.016457	4.9512	4.9673	4.981	0.015052	-0.0366	-0.035	-0.0337	0.0014731

Device Test: 61.6 V_BP7L(V_BP7L PWM 2MHz VIN_12V)

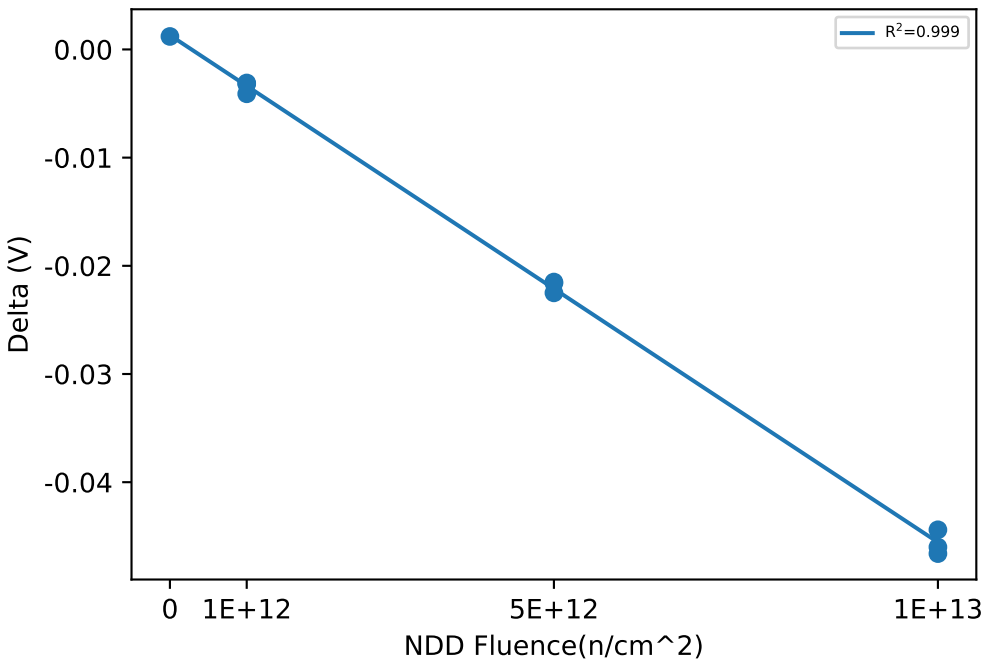
NDD vs Result Stats



Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	6.9992	6.9961	-0.0031
551	1e+12	NDD	6.9998	6.9966	-0.0032
552	1e+12	NDD	7.0611	7.057	-0.0041
553	5e+12	NDD	7.0083	6.9868	-0.0215
554	5e+12	NDD	7.0011	6.9786	-0.0225
555	5e+12	NDD	6.9873	6.9657	-0.0216
556	1e+13	NDD	7.0322	6.9878	-0.0444
557	1e+13	NDD	7.0565	7.0105	-0.046
558	1e+13	NDD	7.0383	6.9917	-0.0466
559	0	NDD, Ctrl	7.0178	7.019	0.0012

NDD vs Post - Pre Exposure Delta

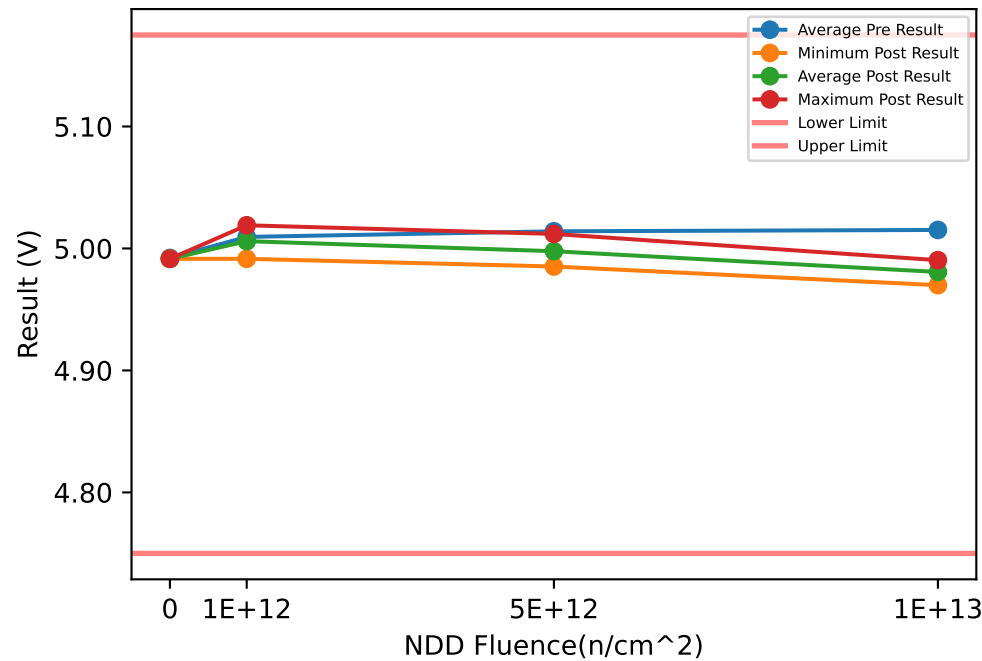


Test Statistics (V)

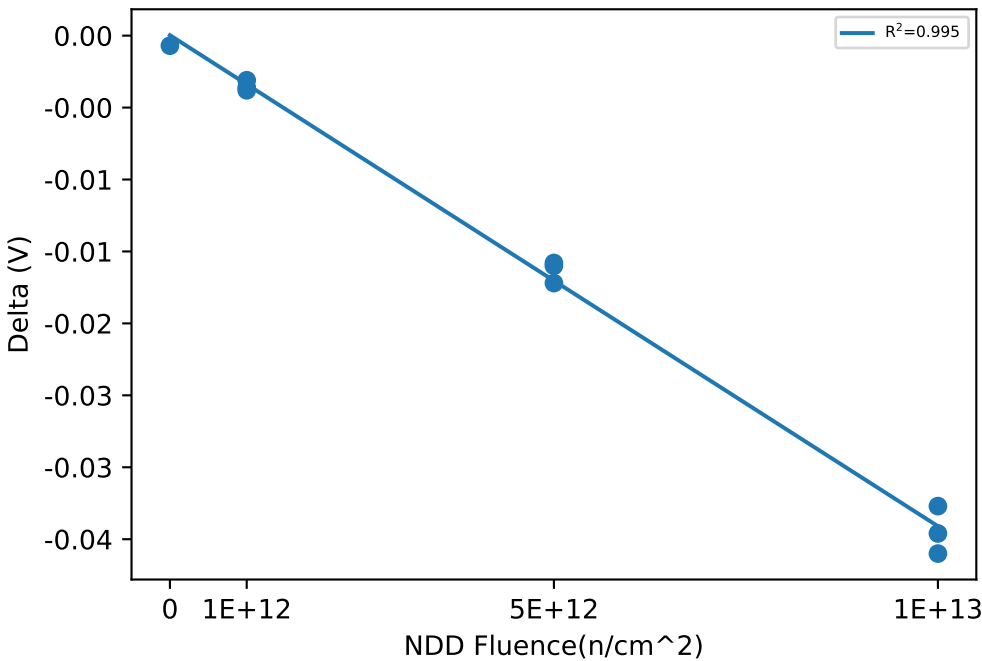
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0178	7.0178	7.0178		7.019	7.019	7.019		0.0012	0.0012	0.0012	
1e+12	6.9992	7.02	7.0611	0.035566	6.9961	7.0166	7.057	0.035017	-0.0041	-0.0034667	-0.0031	0.00055076
5e+12	6.9873	6.9989	7.0083	0.010671	6.9657	6.977	6.9868	0.010637	-0.0225	-0.021867	-0.0215	0.00055076
1e+13	7.0322	7.0423	7.0565	0.012642	6.9878	6.9967	7.0105	0.012138	-0.0466	-0.045667	-0.0444	0.0011372

Device Test: 61.7 V_BP5L(V_BP5L PWM 2MHz VIN_12V)

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

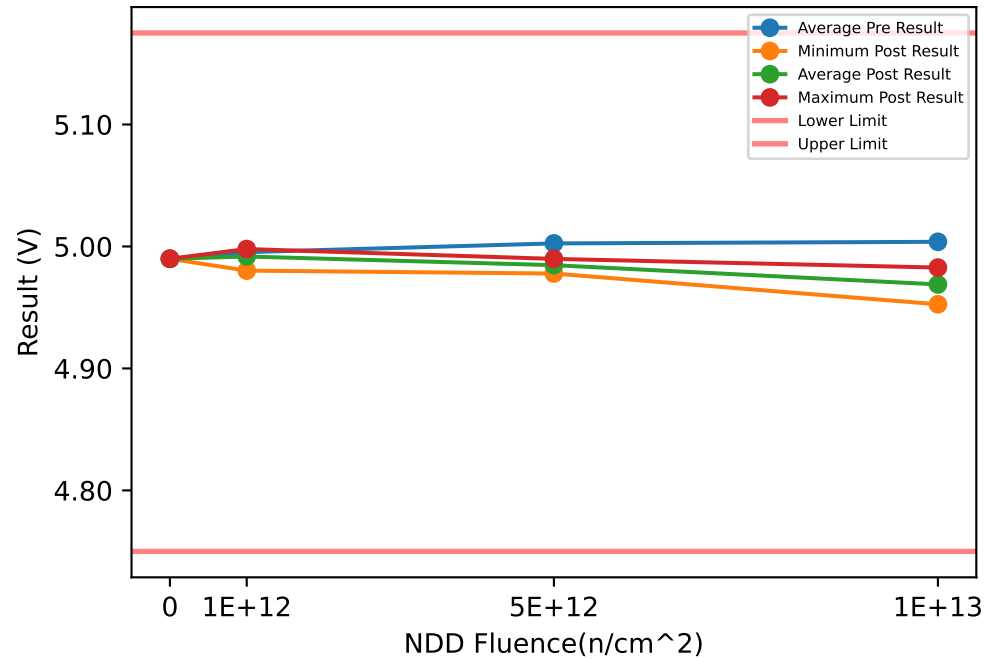
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.9951	4.9915	-0.0036
551	1e+12	NDD	5.0112	5.0074	-0.0038
552	1e+12	NDD	5.0221	5.019	-0.0031
553	5e+12	NDD	5.0119	4.9961	-0.0158
554	5e+12	NDD	5.0024	4.9852	-0.0172
555	5e+12	NDD	5.0279	5.0119	-0.016
556	1e+13	NDD	5.0045	4.9699	-0.0346
557	1e+13	NDD	5.0231	4.9904	-0.0327
558	1e+13	NDD	5.0179	4.9819	-0.036
559	0	NDD, Ctrl	4.9922	4.9915	-0.0007

Test Statistics (V)

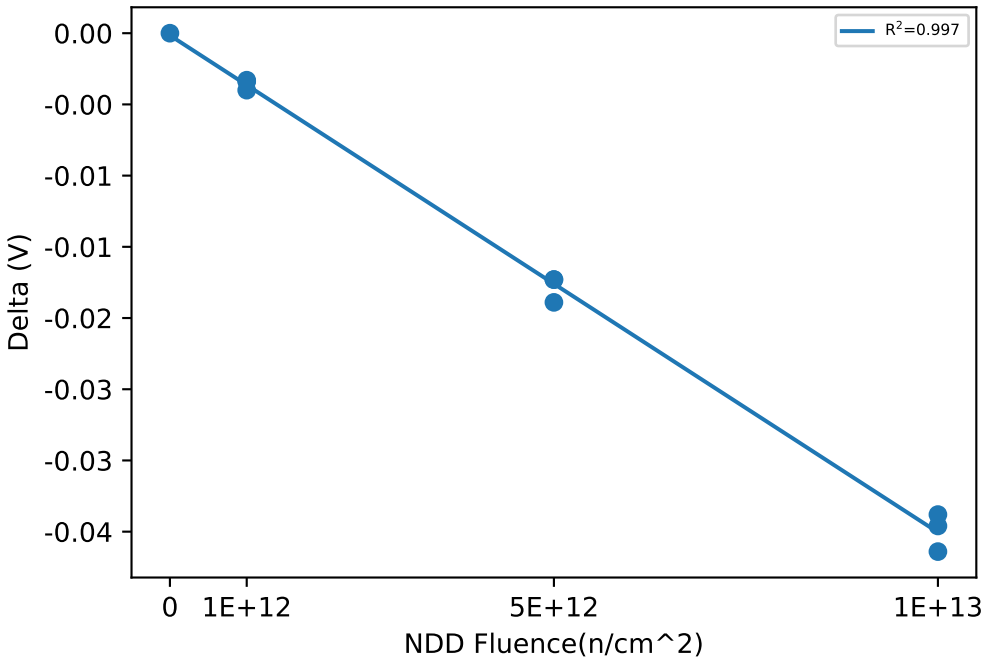
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9922	4.9922	4.9922		4.9915	4.9915	4.9915		-0.0007	-0.0007	-0.0007	
1e+12	4.9951	5.0095	5.0221	0.013583	4.9915	5.006	5.019	0.013806	-0.0038	-0.0035	-0.0031	0.00036056
5e+12	5.0024	5.0141	5.0279	0.012887	4.9852	4.9977	5.0119	0.013425	-0.0172	-0.016333	-0.0158	0.00075719
1e+13	5.0045	5.0152	5.0231	0.0095965	4.9699	4.9807	4.9904	0.0103	-0.036	-0.034433	-0.0327	0.0016563

Device Test: 61.8 V_BP5H(V_BP5H PWM 2MHz VIN_12V)

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

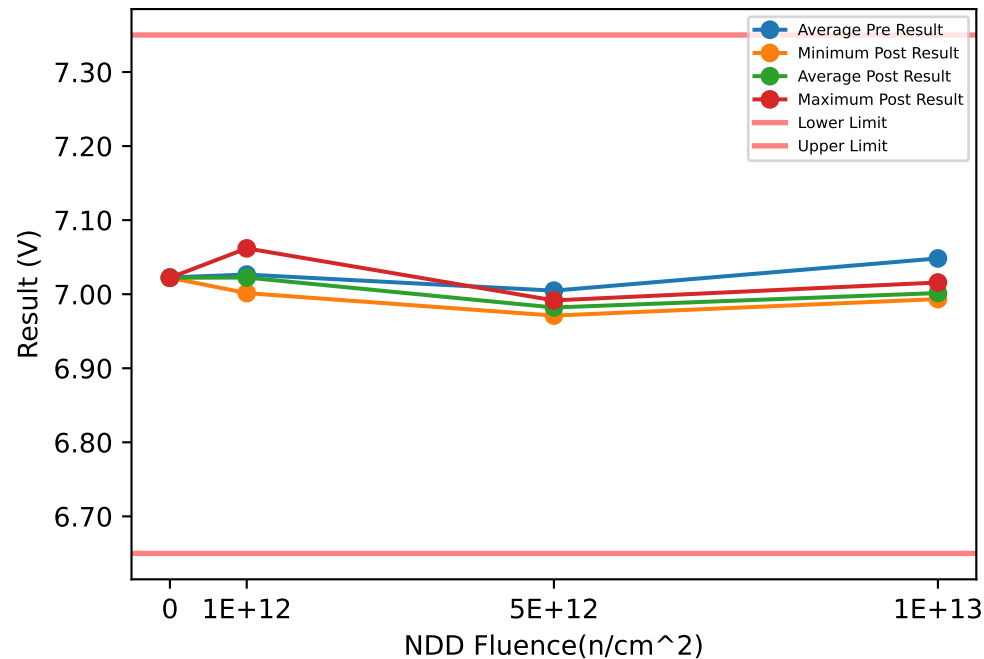
Serial #	Fluence(n/cm ²)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.9842	4.9802	-0.004
551	1e+12	NDD	5.0005	4.9972	-0.0033
552	1e+12	NDD	5.0013	4.9979	-0.0034
553	5e+12	NDD	4.9967	4.9778	-0.0189
554	5e+12	NDD	5.0071	4.9898	-0.0173
555	5e+12	NDD	5.0037	4.9864	-0.0173
556	1e+13	NDD	4.9864	4.9526	-0.0338
557	1e+13	NDD	5.0191	4.9827	-0.0364
558	1e+13	NDD	5.0059	4.9713	-0.0346
559	0	NDD, Ctrl	4.9899	4.9899	0

Test Statistics (V)

Fluence(n/cm ²)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9899	4.9899	4.9899		4.9899	4.9899	4.9899		0	0	0	
1e+12	4.9842	4.9953	5.0013	0.00965	4.9802	4.9918	4.9979	0.010023	-0.004	-0.0035667	-0.0033	0.00037859
5e+12	4.9967	5.0025	5.0071	0.0053028	4.9778	4.9847	4.9898	0.0061849	-0.0189	-0.017833	-0.0173	0.00092376
1e+13	4.9864	5.0038	5.0191	0.016451	4.9526	4.9689	4.9827	0.015197	-0.0364	-0.034933	-0.0338	0.0013317

Device Test: 61.9 V_BP7L(V_BP7L PWM 5MHz VIN_12V)

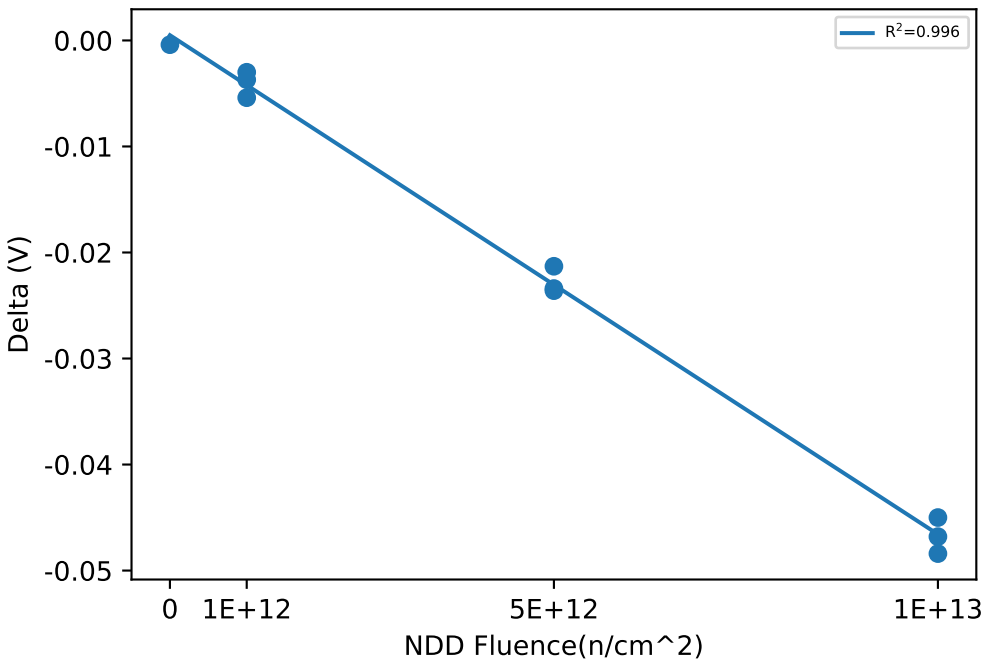
NDD vs Result Stats



Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	7.0052	7.0015	-0.0037
551	1e+12	NDD	7.007	7.004	-0.003
552	1e+12	NDD	7.0673	7.0619	-0.0054
553	5e+12	NDD	7.0129	6.9916	-0.0213
554	5e+12	NDD	7.007	6.9834	-0.0236
555	5e+12	NDD	6.9945	6.9711	-0.0234
556	1e+13	NDD	7.0384	6.9934	-0.045
557	1e+13	NDD	7.0626	7.0158	-0.0468
558	1e+13	NDD	7.0439	6.9955	-0.0484
559	0	NDD, Ctrl	7.0226	7.0222	-0.0004

NDD vs Post - Pre Exposure Delta

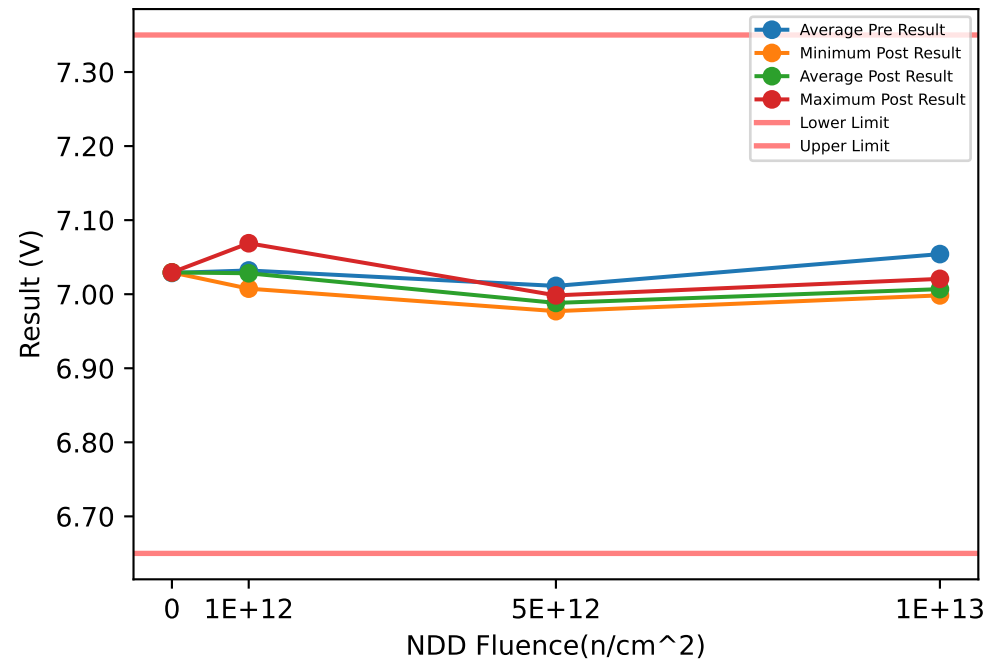


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0226	7.0226	7.0226		7.0222	7.0222	7.0222		-0.0004	-0.0004	-0.0004	
1e+12	7.0052	7.0265	7.0673	0.035345	7.0015	7.0225	7.0619	0.034173	-0.0054	-0.0040333	-0.003	0.0012342
5e+12	6.9945	7.0048	7.0129	0.0093952	6.9711	6.982	6.9916	0.010318	-0.0236	-0.022767	-0.0213	0.0012741
1e+13	7.0384	7.0483	7.0626	0.012686	6.9934	7.0016	7.0158	0.012371	-0.0484	-0.046733	-0.045	0.001701

Device Test: 62.0 V_BP7L(V_BP7L PWM 500kHz VIN_14V)

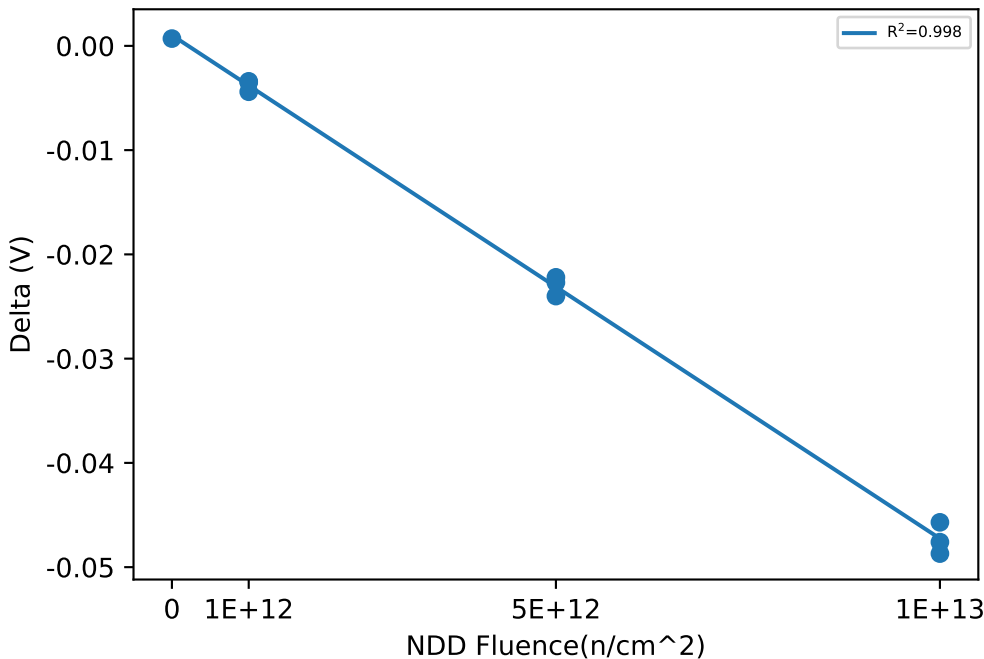
NDD vs Result Stats



Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	7.0109	7.0075	-0.0034
551	1e+12	NDD	7.012	7.0085	-0.0035
552	1e+12	NDD	7.0732	7.0688	-0.0044
553	5e+12	NDD	7.0206	6.9984	-0.0222
554	5e+12	NDD	7.0132	6.9892	-0.024
555	5e+12	NDD	6.9998	6.9771	-0.0227
556	1e+13	NDD	7.0441	6.9984	-0.0457
557	1e+13	NDD	7.0683	7.0207	-0.0476
558	1e+13	NDD	7.0501	7.0014	-0.0487
559	0	NDD, Ctrl	7.0287	7.0294	0.0007

NDD vs Post - Pre Exposure Delta

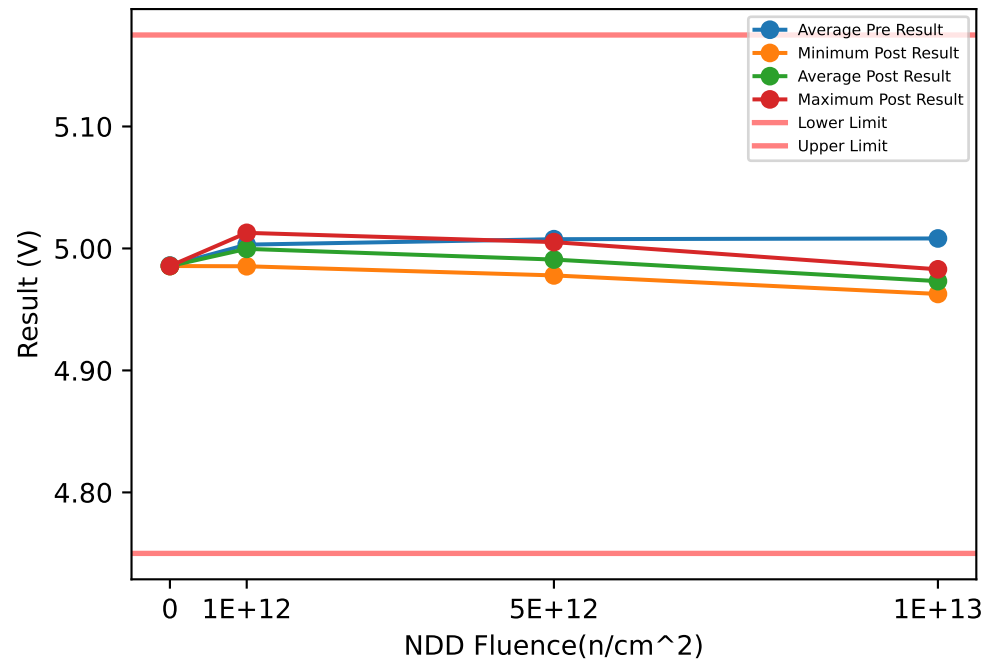


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0287	7.0287	7.0287		7.0294	7.0294	7.0294		0.0007	0.0007	0.0007	
1e+12	7.0109	7.032	7.0732	0.035656	7.0075	7.0283	7.0688	0.035106	-0.0044	-0.0037667	-0.0034	0.00055076
5e+12	6.9998	7.0112	7.0206	0.010543	6.9771	6.9882	6.9984	0.010683	-0.024	-0.022967	-0.0222	0.00092916
1e+13	7.0441	7.0542	7.0683	0.012602	6.9984	7.0068	7.0207	0.012102	-0.0487	-0.047333	-0.0457	0.0015177

Device Test: 62.1 V_BP5L(V_BP5L PWM 500kHz VIN_14V)

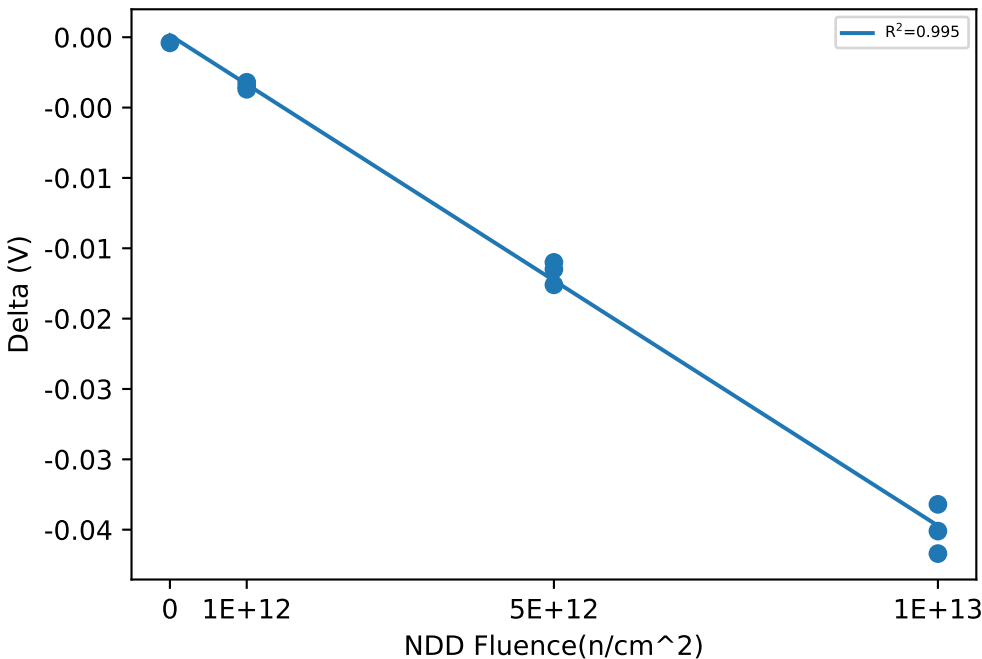
NDD vs Result Stats



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.9889	4.9854	-0.0035
551	1e+12	NDD	5.0045	5.0008	-0.0037
552	1e+12	NDD	5.016	5.0128	-0.0032
553	5e+12	NDD	5.0056	4.9896	-0.016
554	5e+12	NDD	4.9955	4.9779	-0.0176
555	5e+12	NDD	5.0217	5.0052	-0.0165
556	1e+13	NDD	4.9978	4.9627	-0.0351
557	1e+13	NDD	5.0161	4.9829	-0.0332
558	1e+13	NDD	5.0107	4.974	-0.0367
559	0	NDD, Ctrl	4.986	4.9856	-0.0004

NDD vs Post - Pre Exposure Delta

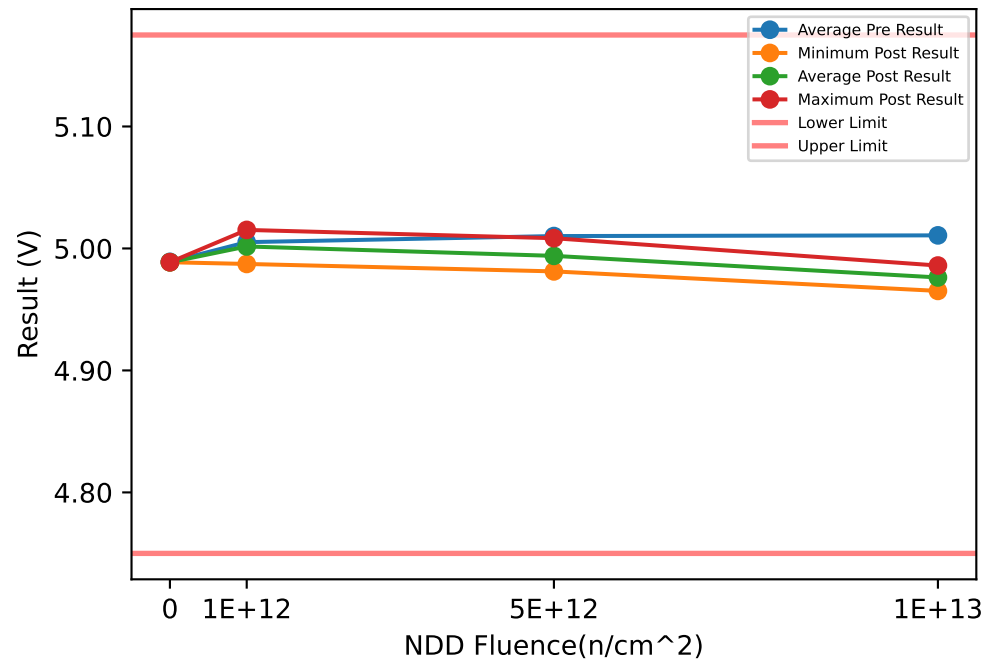


Test Statistics (V)

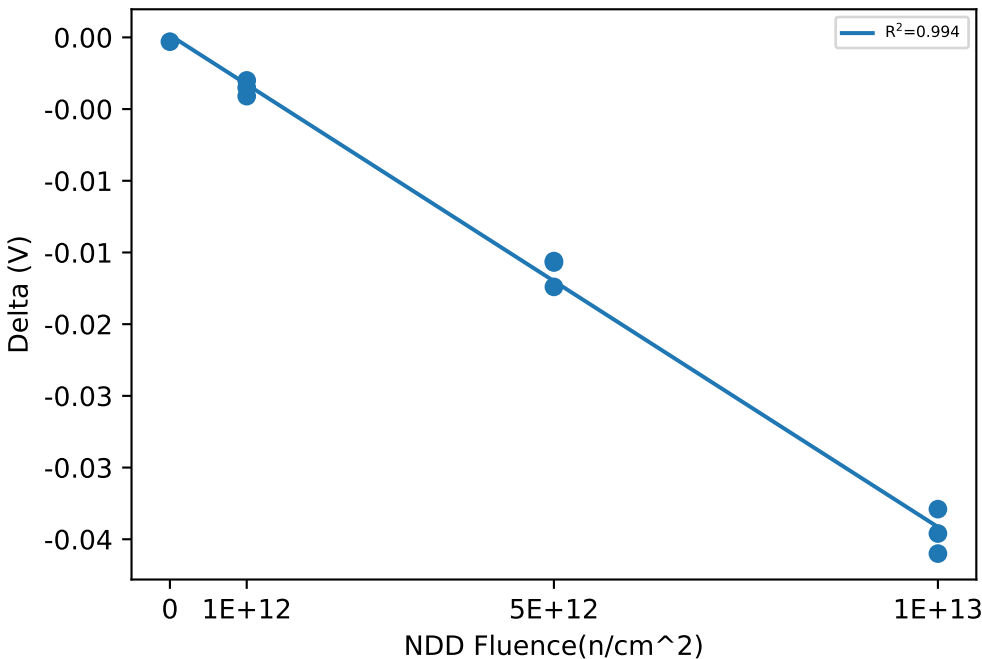
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.986	4.986	4.986		4.9856	4.9856	4.9856		-0.0004	-0.0004	-0.0004	
1e+12	4.9889	5.0031	5.016	0.013602	4.9854	4.9997	5.0128	0.013735	-0.0037	-0.0034667	-0.0032	0.00025166
5e+12	4.9955	5.0076	5.0217	0.013214	4.9779	4.9909	5.0052	0.013696	-0.0176	-0.0167	-0.016	0.00081854
1e+13	4.9978	5.0082	5.0161	0.0094027	4.9627	4.9732	4.9829	0.010124	-0.0367	-0.035	-0.0332	0.0017521

Device Test: 62.10 V_BP5L(V_BP5L PWM 5MHz VIN_14V)

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

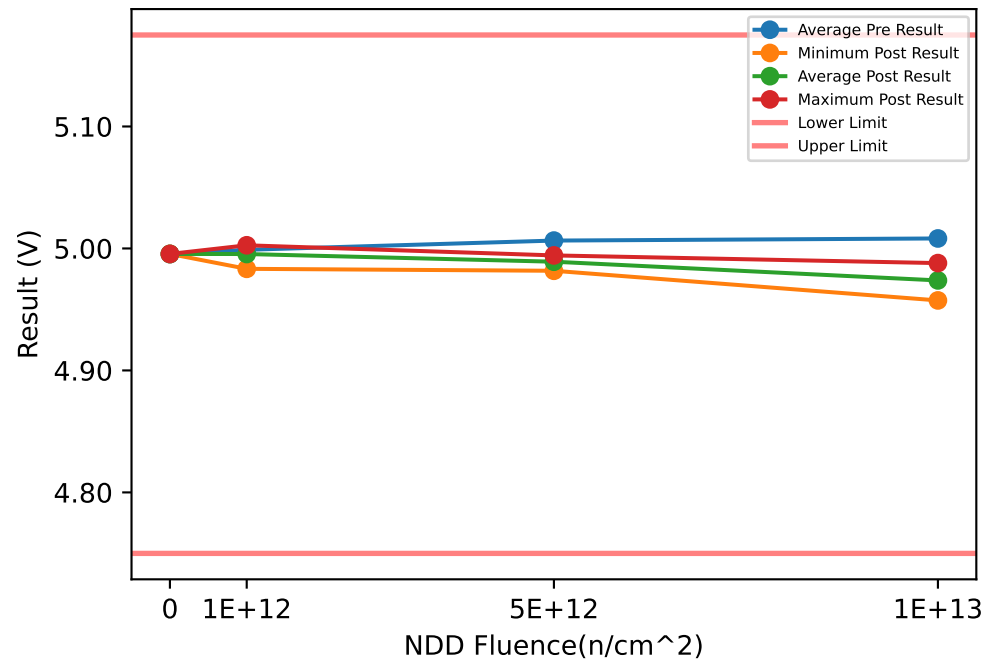
Serial #	Fluence(n/cm ²)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.9908	4.9873	-0.0035
551	1e+12	NDD	5.0065	5.0024	-0.0041
552	1e+12	NDD	5.0182	5.0152	-0.003
553	5e+12	NDD	5.0078	4.9922	-0.0156
554	5e+12	NDD	4.9986	4.9812	-0.0174
555	5e+12	NDD	5.0241	5.0084	-0.0157
556	1e+13	NDD	4.9998	4.9652	-0.0346
557	1e+13	NDD	5.0189	4.986	-0.0329
558	1e+13	NDD	5.0135	4.9775	-0.036
559	0	NDD, Ctrl	4.989	4.9887	-0.0003

Test Statistics (V)

Fluence(n/cm ²)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.989	4.989	4.989		4.9887	4.9887	4.9887		-0.0003	-0.0003	-0.0003	
1e+12	4.9908	5.0052	5.0182	0.013749	4.9873	5.0016	5.0152	0.013966	-0.0041	-0.0035333	-0.003	0.00055076
5e+12	4.9986	5.0102	5.0241	0.012914	4.9812	4.9939	5.0084	0.013683	-0.0174	-0.016233	-0.0156	0.0010116
1e+13	4.9998	5.0107	5.0189	0.009846	4.9652	4.9762	4.986	0.010458	-0.036	-0.0345	-0.0329	0.0015524

Device Test: 62.11 V_BP5H(V_BP5H PWM 5MHz VIN_14V)

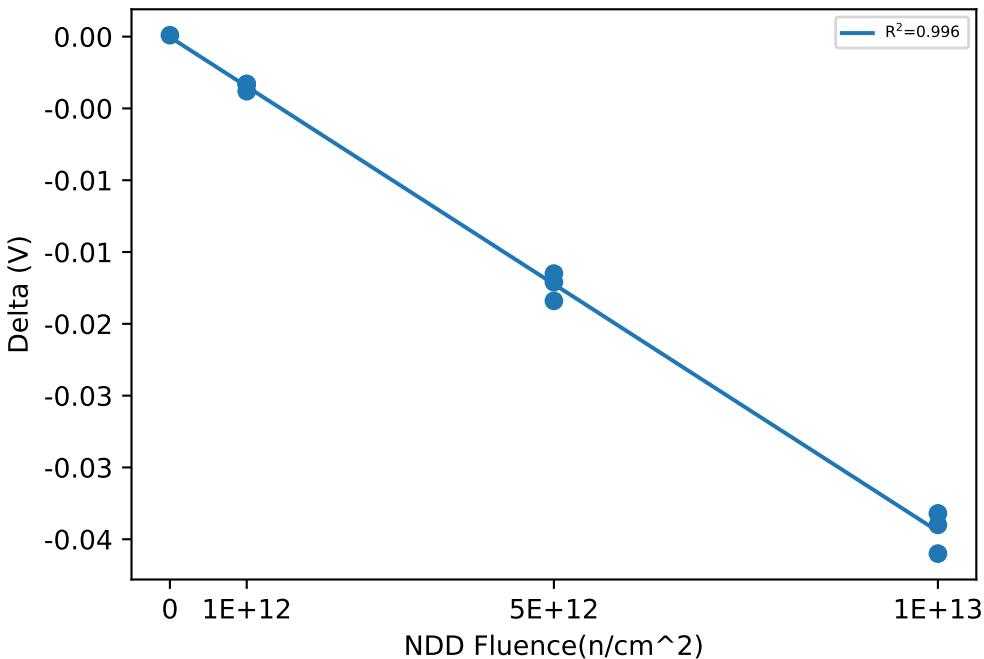
NDD vs Result Stats



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.9871	4.9833	-0.0038
551	1e+12	NDD	5.0037	5.0004	-0.0033
552	1e+12	NDD	5.0059	5.0026	-0.0033
553	5e+12	NDD	5.0001	4.9817	-0.0184
554	5e+12	NDD	5.0114	4.9943	-0.0171
555	5e+12	NDD	5.0079	4.9914	-0.0165
556	1e+13	NDD	4.9906	4.9574	-0.0332
557	1e+13	NDD	5.024	4.988	-0.036
558	1e+13	NDD	5.01	4.976	-0.034
559	0	NDD, Ctrl	4.9954	4.9955	0.0001

NDD vs Post - Pre Exposure Delta

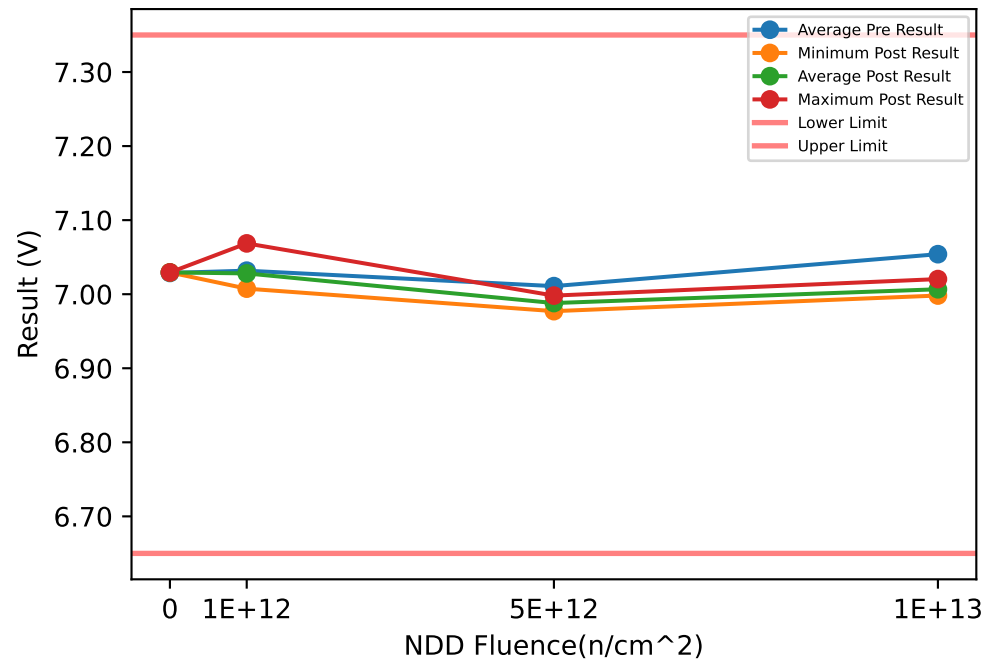


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9954	4.9954	4.9954		4.9955	4.9955	4.9955		0.0001	0.0001	0.0001	
1e+12	4.9871	4.9989	5.0059	0.010278	4.9833	4.9954	5.0026	0.010565	-0.0038	-0.0034667	-0.0033	0.00028868
5e+12	5.0001	5.0065	5.0114	0.0057848	4.9817	4.9891	4.9943	0.0065987	-0.0184	-0.017333	-0.0165	0.00097125
1e+13	4.9906	5.0082	5.024	0.016773	4.9574	4.9738	4.988	0.015418	-0.036	-0.0344	-0.0332	0.0014422

Device Test: 62.12 V_BP7L(V_BP7L IIM 500kHz VIN_14V)

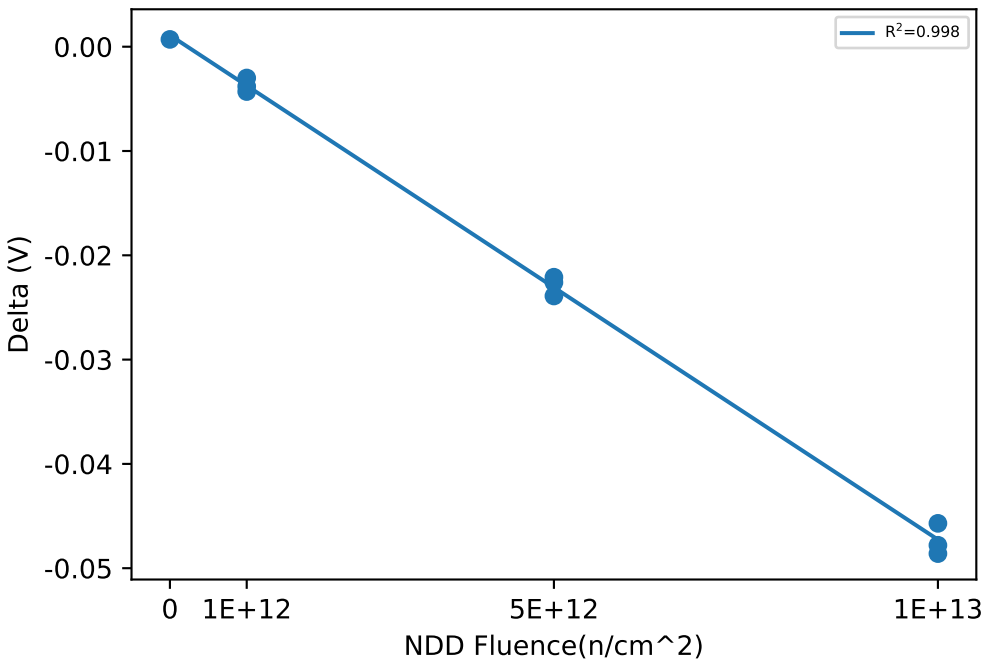
NDD vs Result Stats



Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	7.0105	7.0075	-0.003
551	1e+12	NDD	7.0119	7.0081	-0.0038
552	1e+12	NDD	7.0729	7.0686	-0.0043
553	5e+12	NDD	7.0202	6.9981	-0.0221
554	5e+12	NDD	7.0128	6.9889	-0.0239
555	5e+12	NDD	6.9997	6.9771	-0.0226
556	1e+13	NDD	7.0439	6.9982	-0.0457
557	1e+13	NDD	7.0682	7.0204	-0.0478
558	1e+13	NDD	7.05	7.0014	-0.0486
559	0	NDD, Ctrl	7.0287	7.0294	0.0007

NDD vs Post - Pre Exposure Delta

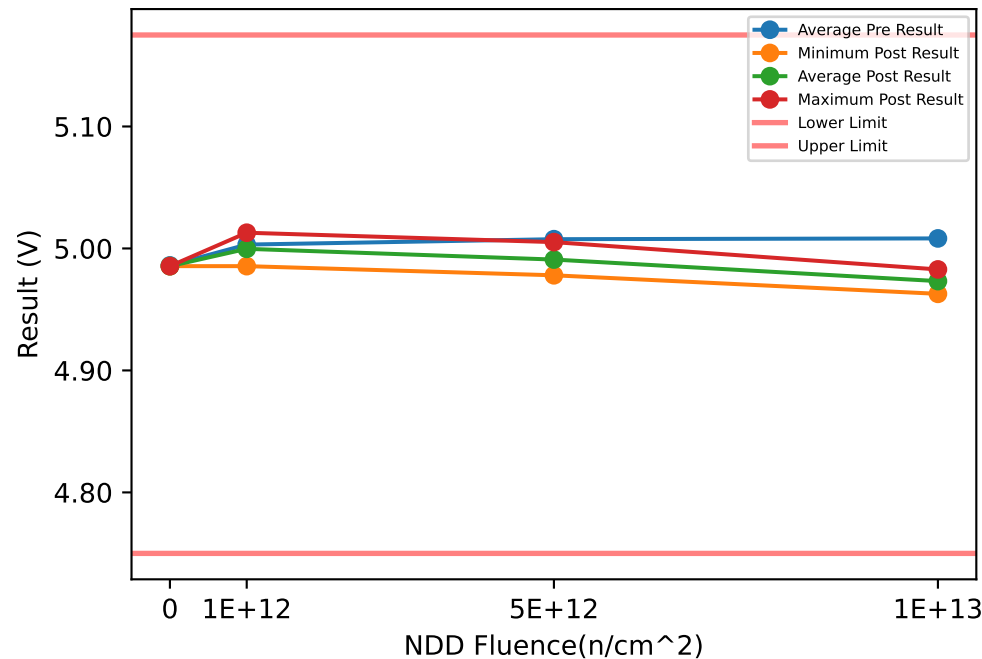


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0287	7.0287	7.0287		7.0294	7.0294	7.0294		0.0007	0.0007	0.0007	
1e+12	7.0105	7.0318	7.0729	0.035629	7.0075	7.0281	7.0686	0.035104	-0.0043	-0.0037	-0.003	0.00065574
5e+12	6.9997	7.0109	7.0202	0.010381	6.9771	6.988	6.9981	0.010527	-0.0239	-0.022867	-0.0221	0.00092916
1e+13	7.0439	7.054	7.0682	0.012642	6.9982	7.0067	7.0204	0.012001	-0.0486	-0.047367	-0.0457	0.0014978

Device Test: 62.13 V_BP5L(V_BP5L IIM 500kHz VIN_14V)

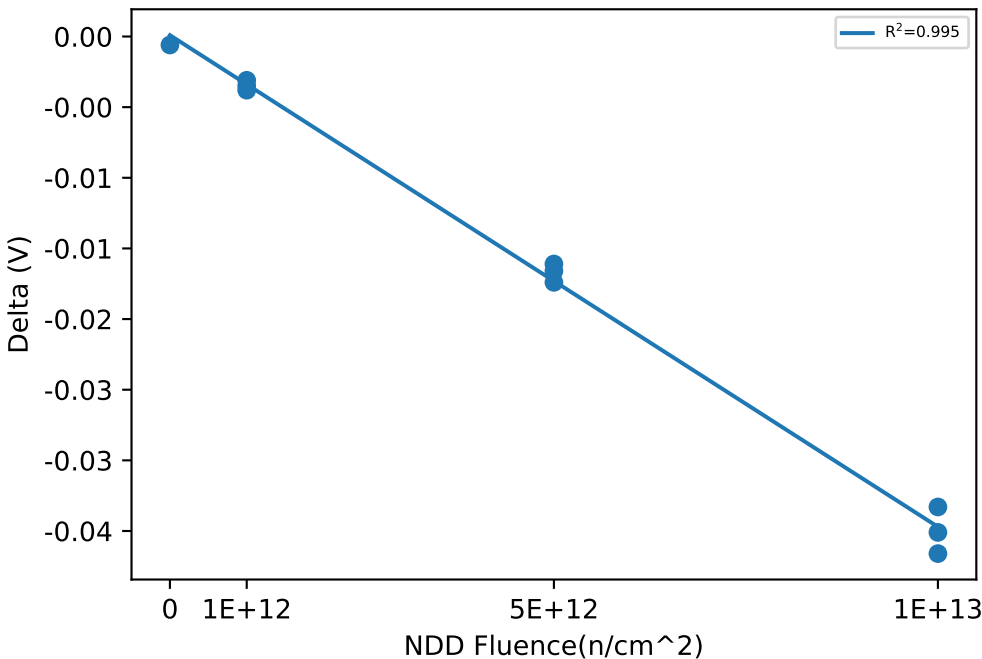
NDD vs Result Stats



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

Serial #	Fluence(n/cm ²)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.989	4.9855	-0.0035
551	1e+12	NDD	5.0045	5.0007	-0.0038
552	1e+12	NDD	5.016	5.0129	-0.0031
553	5e+12	NDD	5.0056	4.9895	-0.0161
554	5e+12	NDD	4.9954	4.978	-0.0174
555	5e+12	NDD	5.0218	5.0052	-0.0166
556	1e+13	NDD	4.9979	4.9628	-0.0351
557	1e+13	NDD	5.0161	4.9828	-0.0333
558	1e+13	NDD	5.0107	4.9741	-0.0366
559	0	NDD, Ctrl	4.9861	4.9855	-0.0006

NDD vs Post - Pre Exposure Delta

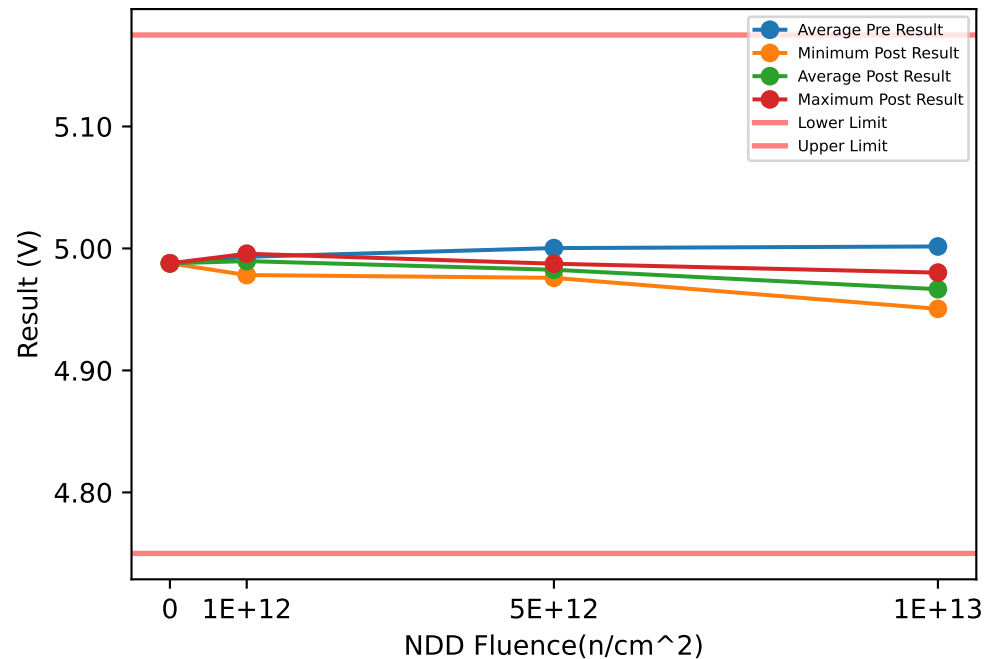


Test Statistics (V)

Fluence(n/cm ²)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9861	4.9861	4.9861		4.9855	4.9855	4.9855		-0.0006	-0.0006	-0.0006	
1e+12	4.989	5.0032	5.016	0.013549	4.9855	4.9997	5.0129	0.013727	-0.0038	-0.0034667	-0.0031	0.00035119
5e+12	4.9954	5.0076	5.0218	0.013313	4.978	4.9909	5.0052	0.013654	-0.0174	-0.0167	-0.0161	0.00065574
1e+13	4.9979	5.0082	5.0161	0.0093474	4.9628	4.9732	4.9828	0.010028	-0.0366	-0.035	-0.0333	0.0016523

Device Test: 62.14 V_BP5H(V_BP5H IIM 500kHz VIN_14V)

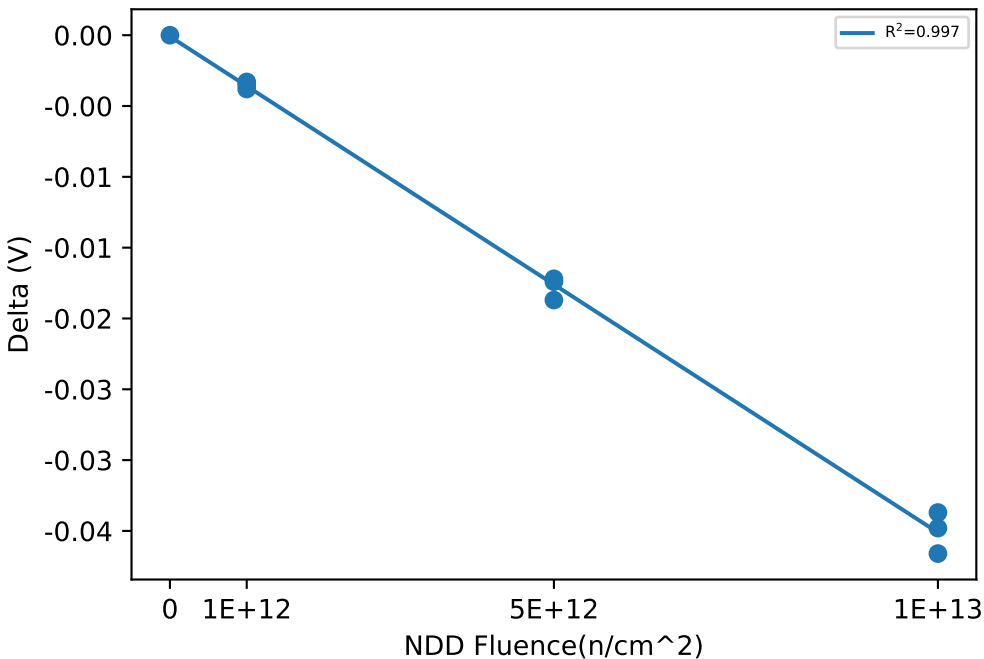
NDD vs Result Stats



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.982	4.9782	-0.0038
551	1e+12	NDD	4.9983	4.995	-0.0033
552	1e+12	NDD	4.9992	4.9957	-0.0035
553	5e+12	NDD	4.9946	4.9759	-0.0187
554	5e+12	NDD	5.0049	4.9875	-0.0174
555	5e+12	NDD	5.0014	4.9842	-0.0172
556	1e+13	NDD	4.9842	4.9505	-0.0337
557	1e+13	NDD	5.0168	4.9802	-0.0366
558	1e+13	NDD	5.0039	4.9691	-0.0348
559	0	NDD, Ctrl	4.9878	4.9878	0

NDD vs Post - Pre Exposure Delta

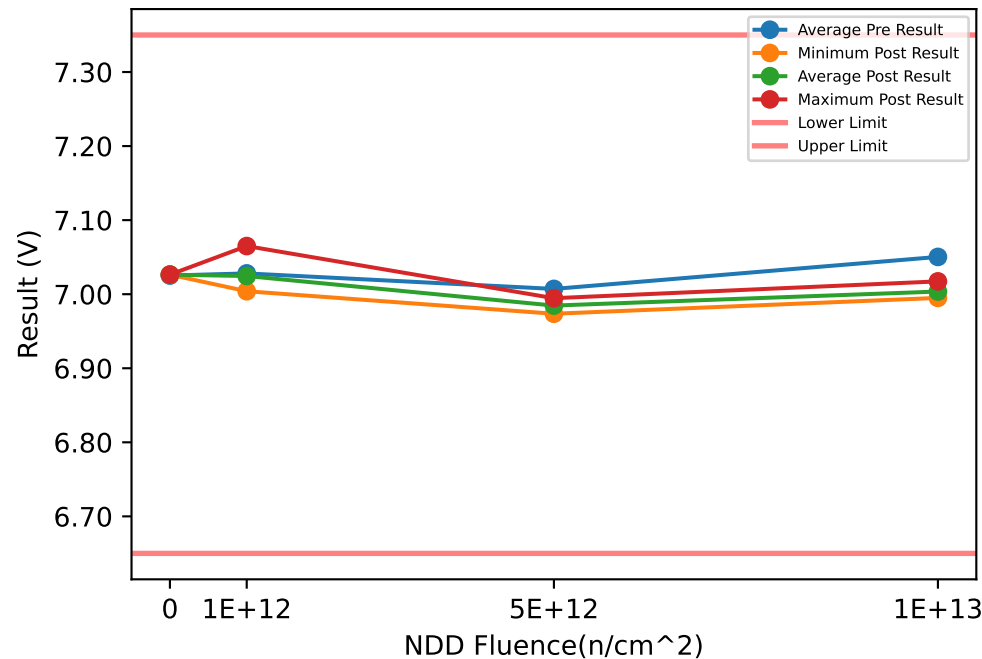


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9878	4.9878	4.9878		4.9878	4.9878	4.9878		0	0	0	
1e+12	4.982	4.9932	4.9992	0.0096811	4.9782	4.9896	4.9957	0.0099077	-0.0038	-0.0035333	-0.0033	0.00025166
5e+12	4.9946	5.0003	5.0049	0.0052374	4.9759	4.9825	4.9875	0.0059769	-0.0187	-0.017767	-0.0172	0.00081445
1e+13	4.9842	5.0016	5.0168	0.016418	4.9505	4.9666	4.9802	0.015007	-0.0366	-0.035033	-0.0337	0.001464

Device Test: 62.15 V_BP7L(V_BP7L IIM 1MHz VIN_14V)

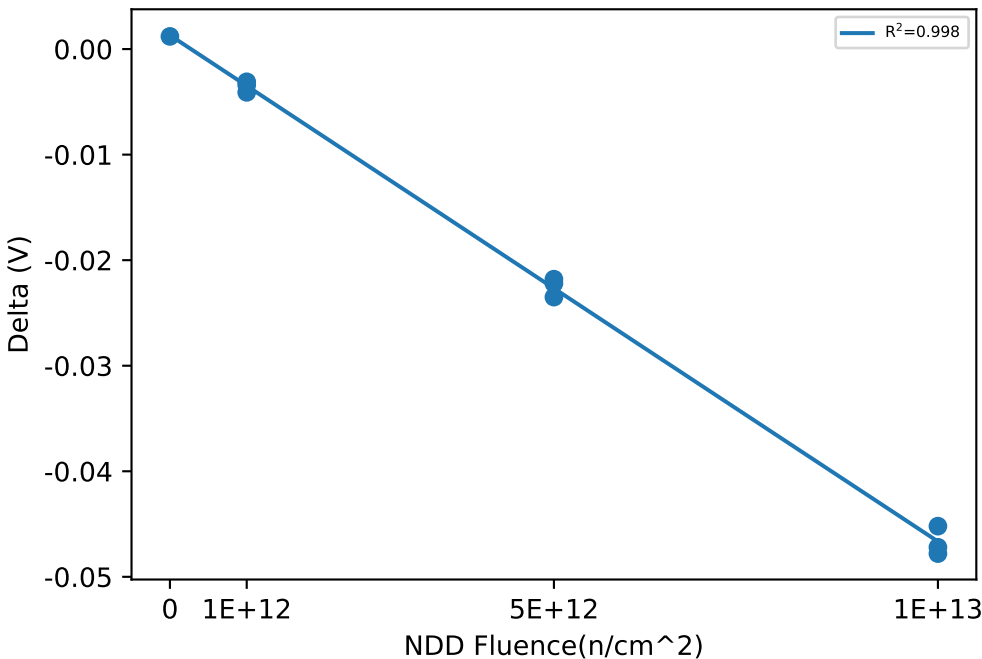
NDD vs Result Stats



Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	7.0071	7.004	-0.0031
551	1e+12	NDD	7.008	7.0046	-0.0034
552	1e+12	NDD	7.0691	7.065	-0.0041
553	5e+12	NDD	7.0164	6.9946	-0.0218
554	5e+12	NDD	7.0092	6.9857	-0.0235
555	5e+12	NDD	6.9958	6.9736	-0.0222
556	1e+13	NDD	7.0402	6.995	-0.0452
557	1e+13	NDD	7.0645	7.0173	-0.0472
558	1e+13	NDD	7.0463	6.9985	-0.0478
559	0	NDD, Ctrl	7.0252	7.0264	0.0012

NDD vs Post - Pre Exposure Delta

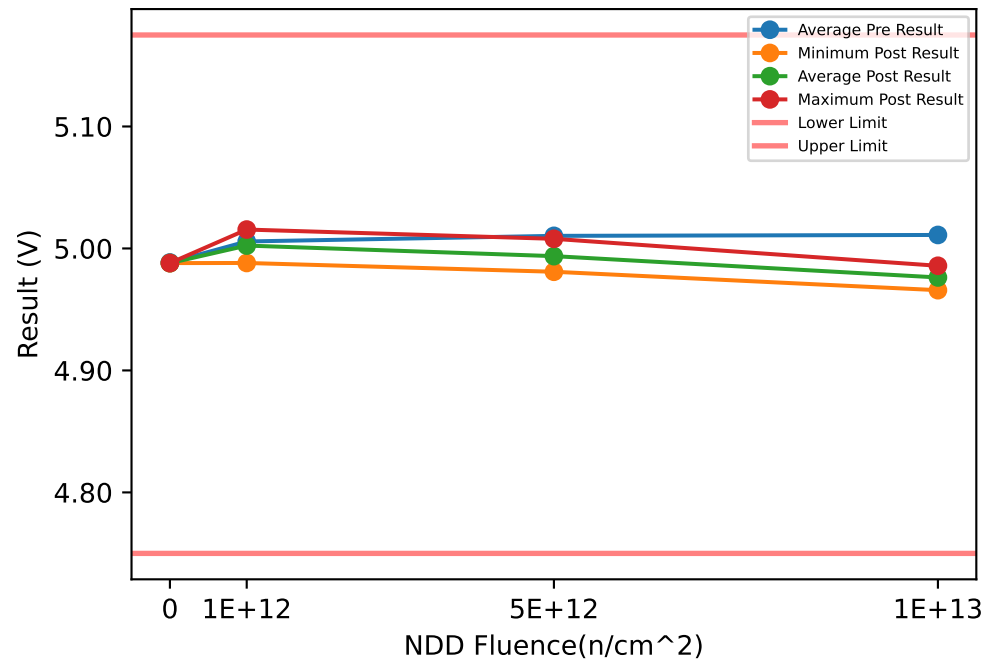


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0252	7.0252	7.0252		7.0264	7.0264	7.0264		0.0012	0.0012	0.0012	
1e+12	7.0071	7.0281	7.0691	0.035539	7.004	7.0245	7.065	0.035046	-0.0041	-0.0035333	-0.0031	0.00051316
5e+12	6.9958	7.0071	7.0164	0.010454	6.9736	6.9846	6.9946	0.010541	-0.0235	-0.0225	-0.0218	0.00088882
1e+13	7.0402	7.0503	7.0645	0.012642	6.995	7.0036	7.0173	0.011993	-0.0478	-0.046733	-0.0452	0.0013614

Device Test: 62.16 V_BP5L(V_BP5L IIM 1MHz VIN_14V)

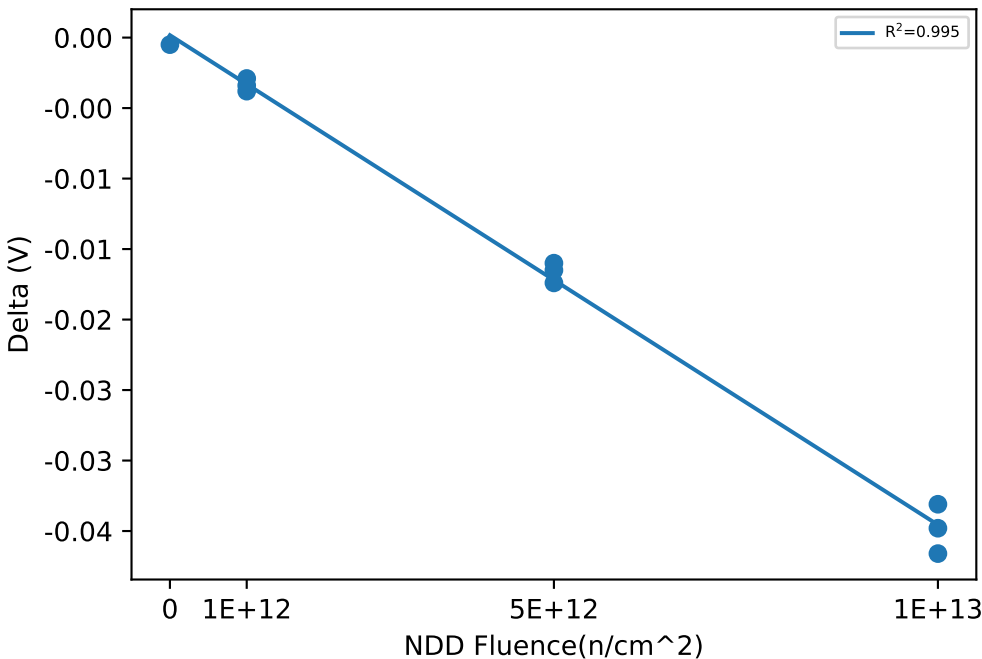
NDD vs Result Stats



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.9915	4.9881	-0.0034
551	1e+12	NDD	5.0073	5.0035	-0.0038
552	1e+12	NDD	5.0184	5.0155	-0.0029
553	5e+12	NDD	5.0083	4.9923	-0.016
554	5e+12	NDD	4.9983	4.9809	-0.0174
555	5e+12	NDD	5.0244	5.0079	-0.0165
556	1e+13	NDD	5.0006	4.9658	-0.0348
557	1e+13	NDD	5.0189	4.9858	-0.0331
558	1e+13	NDD	5.0137	4.9771	-0.0366
559	0	NDD, Ctrl	4.9885	4.988	-0.0005

NDD vs Post - Pre Exposure Delta

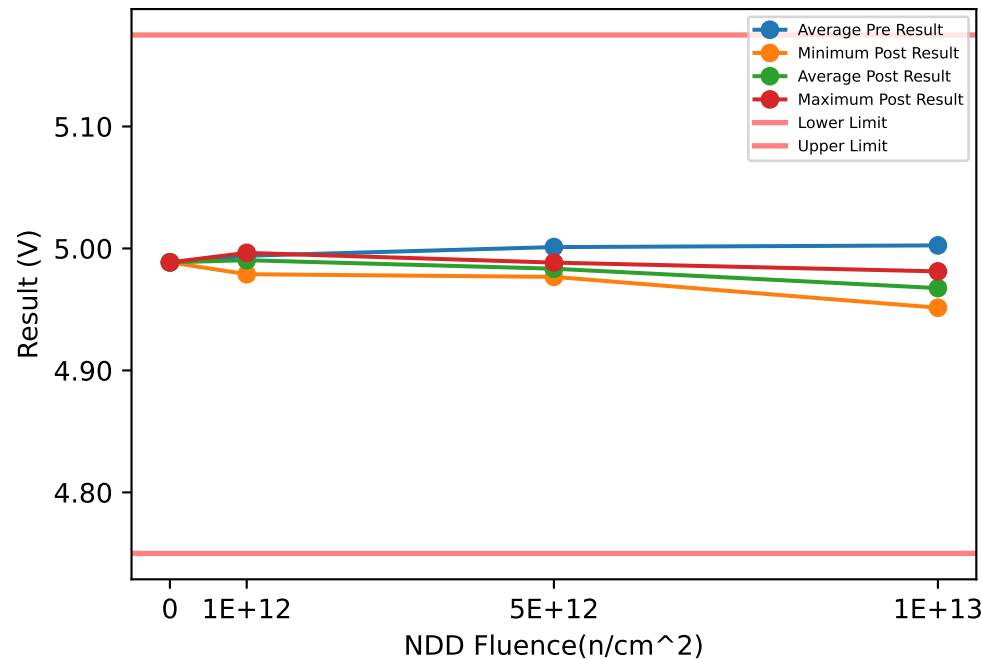


Test Statistics (V)

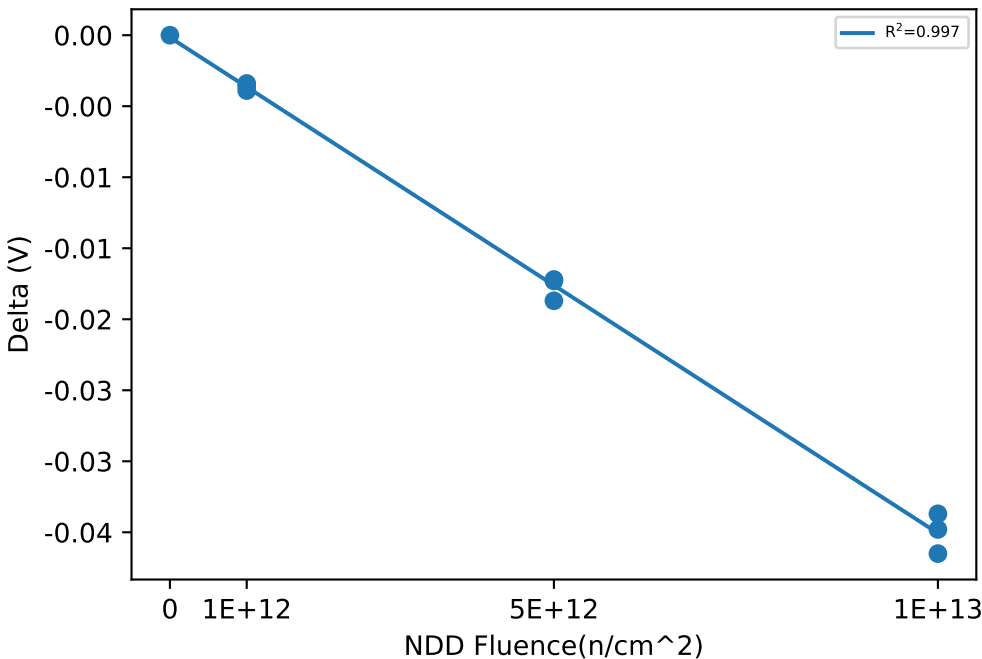
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9885	4.9885	4.9885		4.988	4.988	4.988		-0.0005	-0.0005	-0.0005	
1e+12	4.9915	5.0057	5.0184	0.013518	4.9881	5.0024	5.0155	0.013735	-0.0038	-0.0033667	-0.0029	0.00045092
5e+12	4.9983	5.0103	5.0244	0.013168	4.9809	4.9937	5.0079	0.013554	-0.0174	-0.016633	-0.016	0.00070946
1e+13	5.0006	5.0111	5.0189	0.0094299	4.9658	4.9762	4.9858	0.010028	-0.0366	-0.034833	-0.0331	0.0017502

Device Test: 62.17 V_BP5H(V_BP5H IIM 1MHz VIN_14V)

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

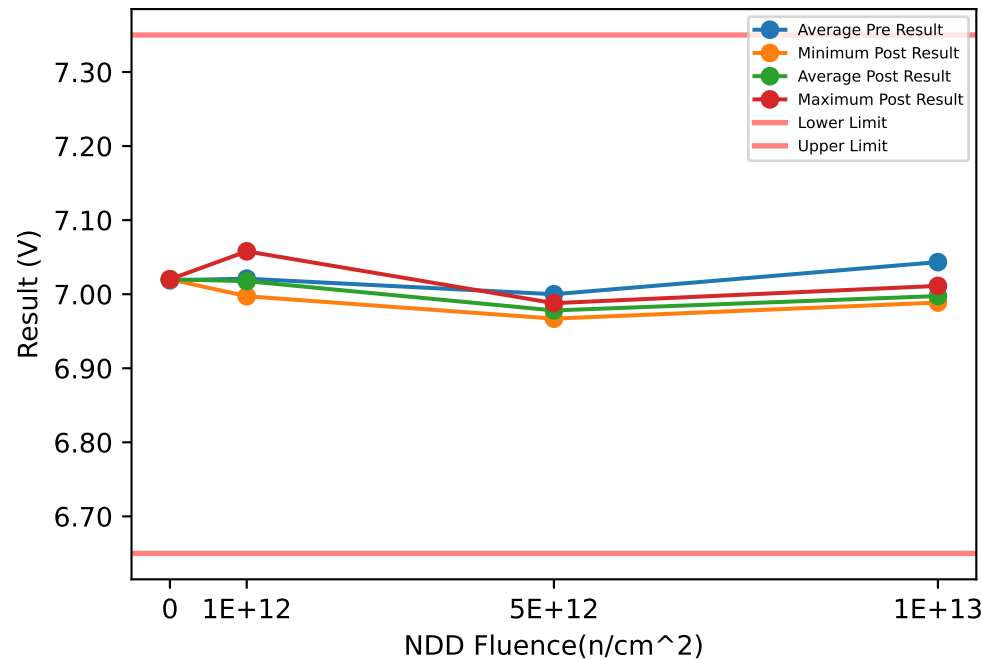
Serial #	Fluence(n/cm ²)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.9828	4.9789	-0.0039
551	1e+12	NDD	4.9992	4.9958	-0.0034
552	1e+12	NDD	5	4.9964	-0.0036
553	5e+12	NDD	4.9954	4.9767	-0.0187
554	5e+12	NDD	5.0057	4.9884	-0.0173
555	5e+12	NDD	5.0023	4.9851	-0.0172
556	1e+13	NDD	4.9851	4.9514	-0.0337
557	1e+13	NDD	5.0177	4.9812	-0.0365
558	1e+13	NDD	5.0047	4.9699	-0.0348
559	0	NDD, Ctrl	4.9886	4.9886	0

Test Statistics (V)

Fluence(n/cm ²)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9886	4.9886	4.9886		4.9886	4.9886	4.9886		0	0	0	
1e+12	4.9828	4.994	5	0.0097077	4.9789	4.9904	4.9964	0.009935	-0.0039	-0.0036333	-0.0034	0.00025166
5e+12	4.9954	5.0011	5.0057	0.0052482	4.9767	4.9834	4.9884	0.0060324	-0.0187	-0.017733	-0.0172	0.00083865
1e+13	4.9851	5.0025	5.0177	0.016411	4.9514	4.9675	4.9812	0.015044	-0.0365	-0.035	-0.0337	0.0014107

Device Test: 62.18 V_BP7L(V_BP7L IIM 2MHz VIN_14V)

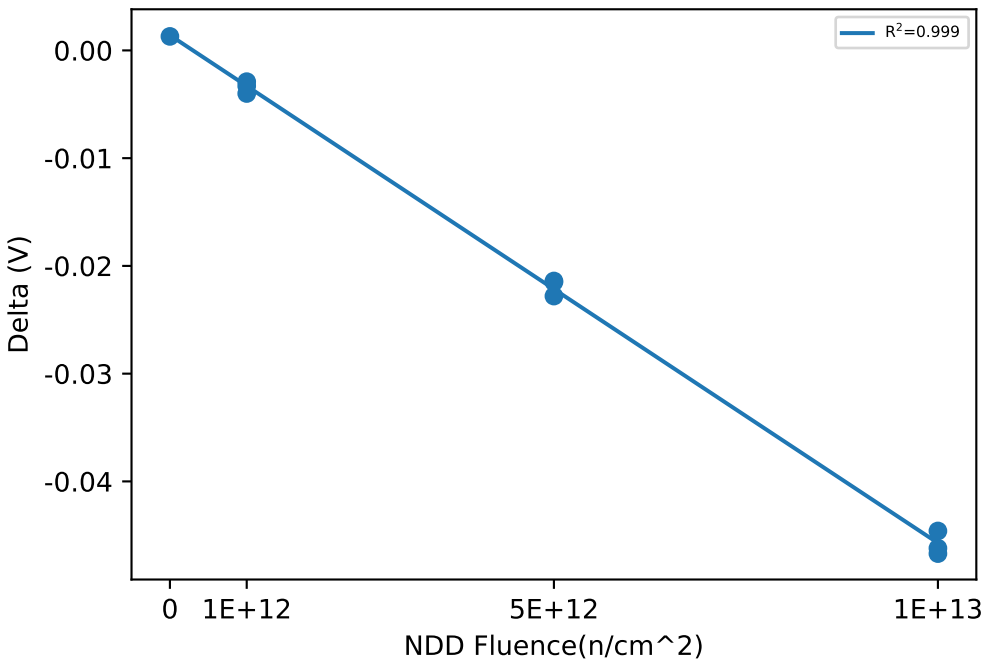
NDD vs Result Stats



Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	7.0002	6.9973	-0.0029
551	1e+12	NDD	7.0008	6.9975	-0.0033
552	1e+12	NDD	7.0619	7.0579	-0.004
553	5e+12	NDD	7.0093	6.9879	-0.0214
554	5e+12	NDD	7.0021	6.9793	-0.0228
555	5e+12	NDD	6.9885	6.967	-0.0215
556	1e+13	NDD	7.0333	6.9887	-0.0446
557	1e+13	NDD	7.0574	7.0112	-0.0462
558	1e+13	NDD	7.0393	6.9926	-0.0467
559	0	NDD, Ctrl	7.0188	7.0201	0.0013

NDD vs Post - Pre Exposure Delta

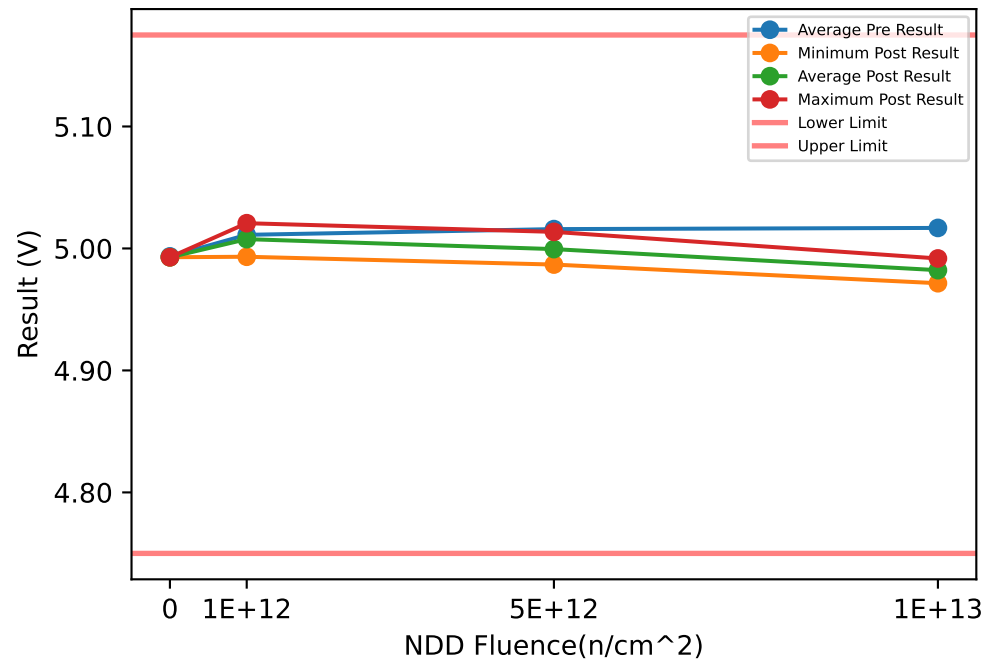


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0188	7.0188	7.0188		7.0201	7.0201	7.0201		0.0013	0.0013	0.0013	
1e+12	7.0002	7.021	7.0619	0.035451	6.9973	7.0176	7.0579	0.03493	-0.004	-0.0034	-0.0029	0.00055678
5e+12	6.9885	7	7.0093	0.010563	6.967	6.9781	6.9879	0.010504	-0.0228	-0.0219	-0.0214	0.00078102
1e+13	7.0333	7.0433	7.0574	0.012546	6.9887	6.9975	7.0112	0.012024	-0.0467	-0.045833	-0.0446	0.001097

Device Test: 62.19 V_BP5L(V_BP5L IIM 2MHz VIN_14V)

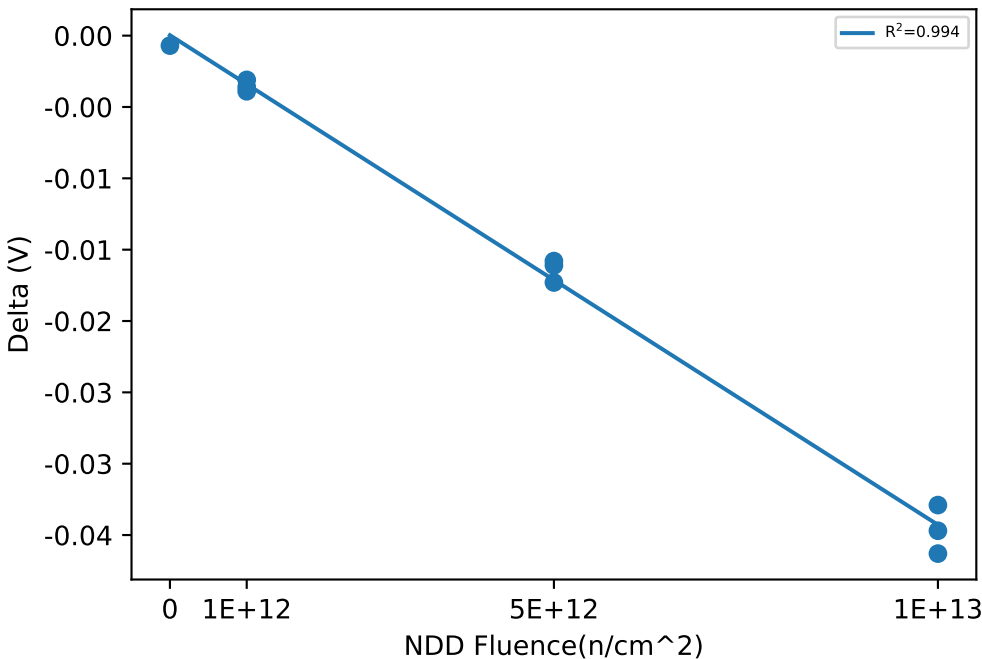
NDD vs Result Stats



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.9968	4.9932	-0.0036
551	1e+12	NDD	5.0129	5.009	-0.0039
552	1e+12	NDD	5.0238	5.0207	-0.0031
553	5e+12	NDD	5.0138	4.998	-0.0158
554	5e+12	NDD	5.0041	4.9868	-0.0173
555	5e+12	NDD	5.0297	5.0136	-0.0161
556	1e+13	NDD	5.0062	4.9715	-0.0347
557	1e+13	NDD	5.0247	4.9918	-0.0329
558	1e+13	NDD	5.0196	4.9833	-0.0363
559	0	NDD, Ctrl	4.9935	4.9928	-0.0007

NDD vs Post - Pre Exposure Delta

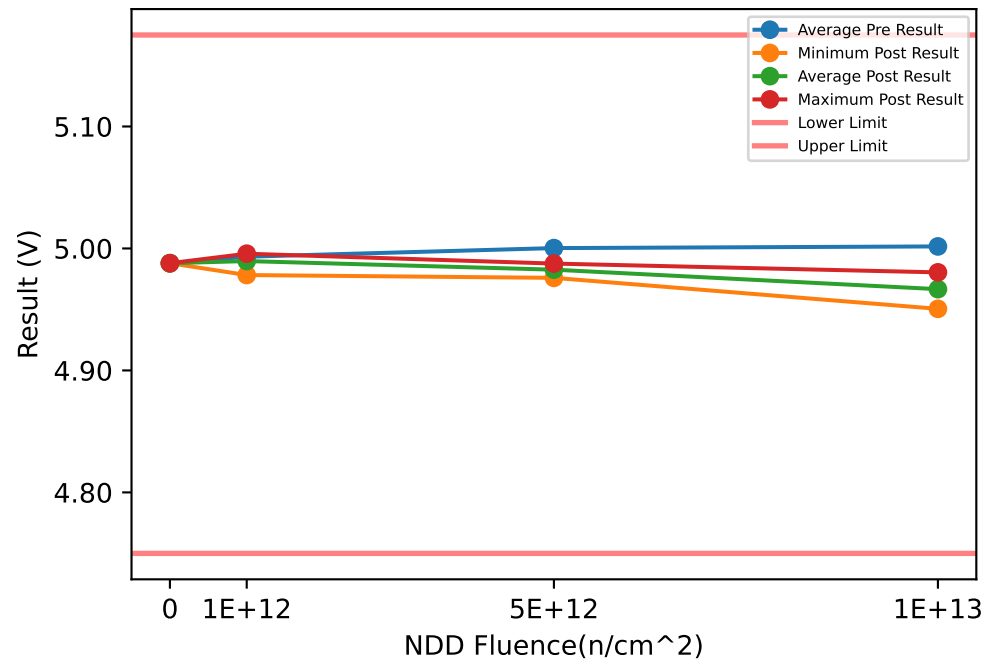


Test Statistics (V)

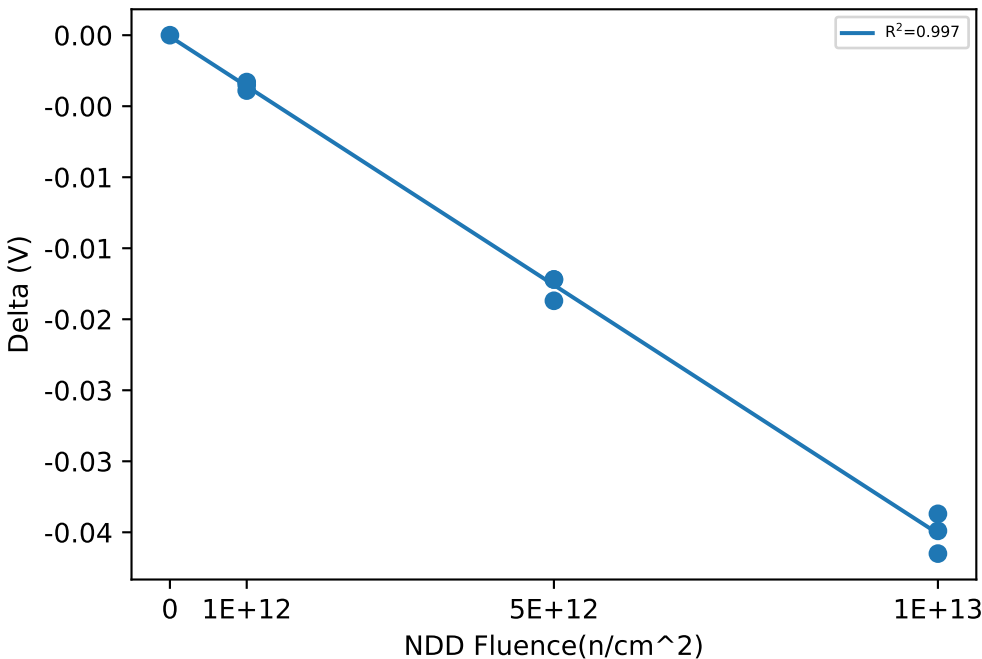
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9935	4.9935	4.9935		4.9928	4.9928	4.9928		-0.0007	-0.0007	-0.0007	
1e+12	4.9968	5.0112	5.0238	0.013583	4.9932	5.0076	5.0207	0.013801	-0.0039	-0.0035333	-0.0031	0.00040415
5e+12	5.0041	5.0159	5.0297	0.012925	4.9868	4.9995	5.0136	0.01346	-0.0173	-0.0164	-0.0158	0.00079373
1e+13	5.0062	5.0168	5.0247	0.0095553	4.9715	4.9822	4.9918	0.010195	-0.0363	-0.034633	-0.0329	0.001701

Device Test: 62.2 V_BP5H(V_BP5H PWM 500kHz VIN_14V)

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

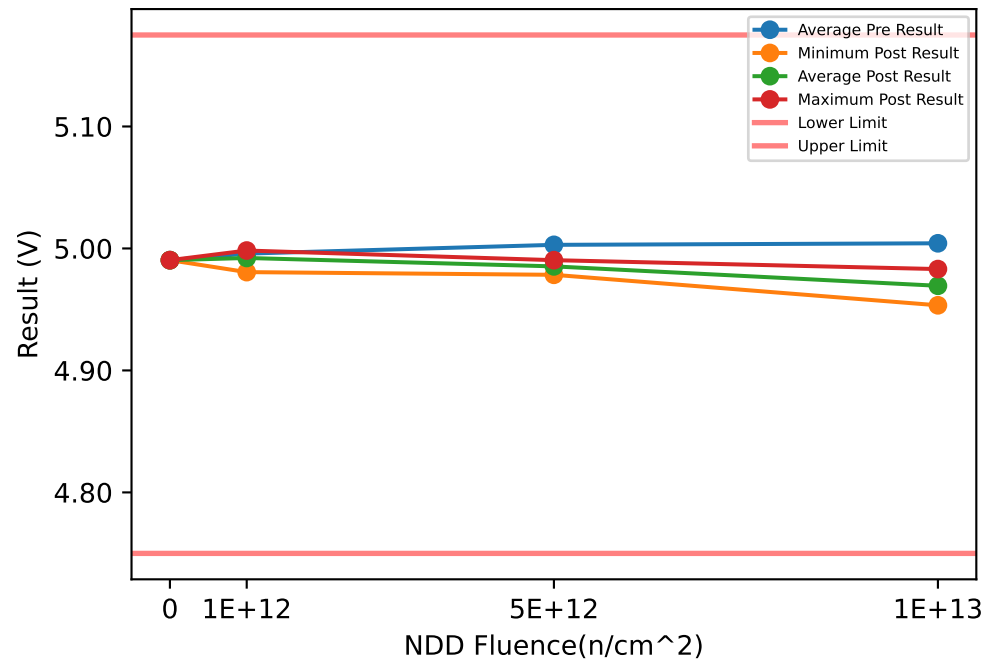
Serial #	Fluence(n/cm ²)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.9821	4.9782	-0.0039
551	1e+12	NDD	4.9984	4.9951	-0.0033
552	1e+12	NDD	4.9992	4.9957	-0.0035
553	5e+12	NDD	4.9946	4.9759	-0.0187
554	5e+12	NDD	5.0048	4.9876	-0.0172
555	5e+12	NDD	5.0015	4.9843	-0.0172
556	1e+13	NDD	4.9842	4.9505	-0.0337
557	1e+13	NDD	5.0169	4.9804	-0.0365
558	1e+13	NDD	5.0039	4.969	-0.0349
559	0	NDD, Ctrl	4.9879	4.9879	0

Test Statistics (V)

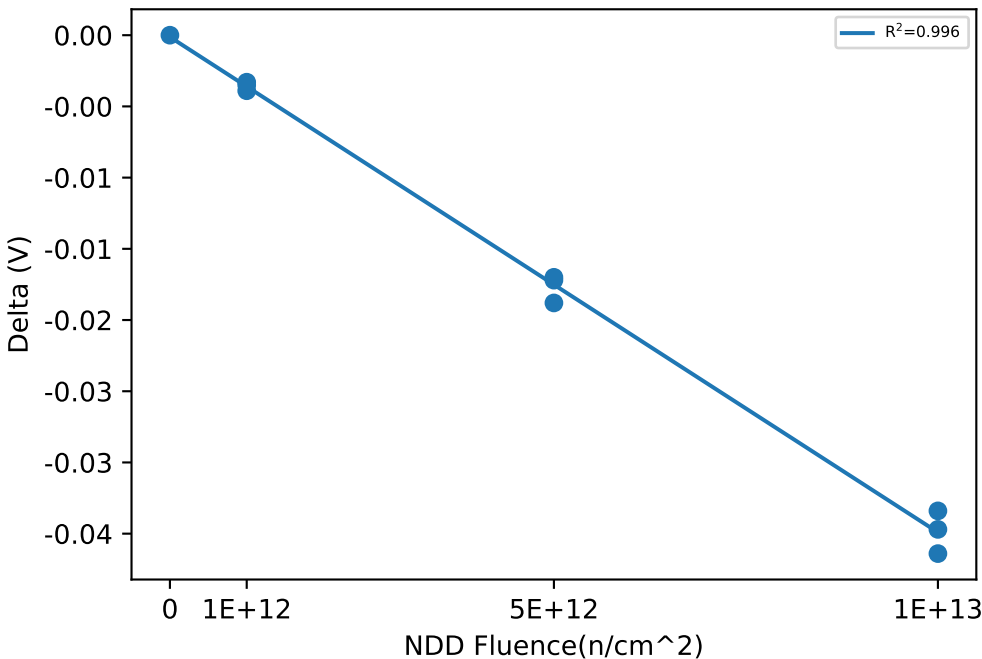
Fluence(n/cm ²)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9879	4.9879	4.9879		4.9879	4.9879	4.9879		0	0	0	
1e+12	4.9821	4.9932	4.9992	0.00965	4.9782	4.9897	4.9957	0.009935	-0.0039	-0.0035667	-0.0033	0.00030551
5e+12	4.9946	5.0003	5.0048	0.0052048	4.9759	4.9826	4.9876	0.0060324	-0.0187	-0.0177	-0.0172	0.00086603
1e+13	4.9842	5.0017	5.0169	0.016464	4.9505	4.9666	4.9804	0.01509	-0.0365	-0.035033	-0.0337	0.0014048

Device Test: 62.20 V_BP5H(V_BP5H IIM 2MHz VIN_14V)

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

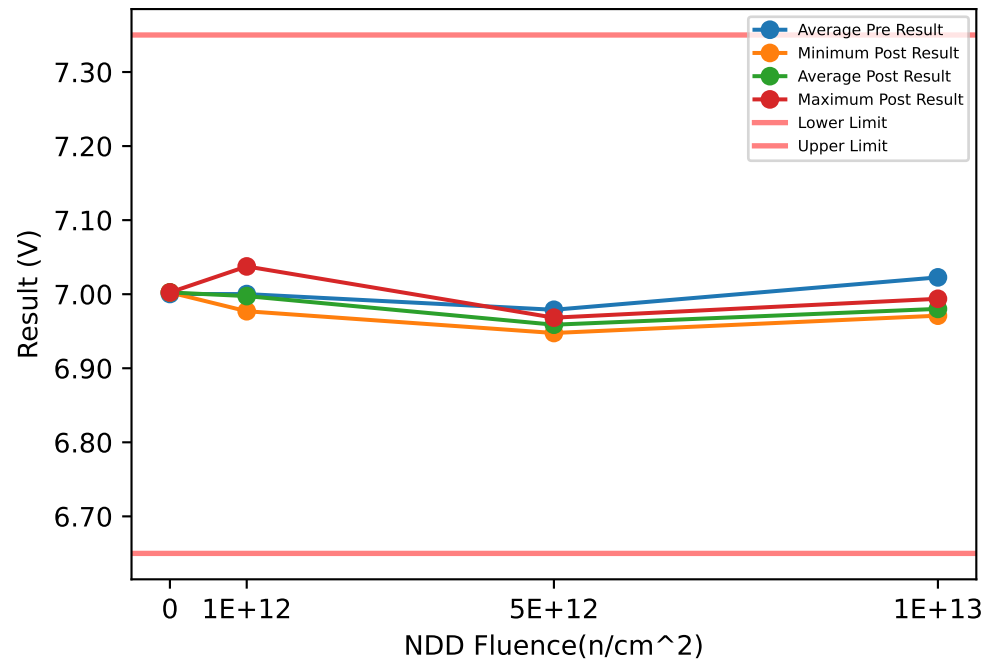
Serial #	Fluence(n/cm ²)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.9845	4.9806	-0.0039
551	1e+12	NDD	5.001	4.9977	-0.0033
552	1e+12	NDD	5.0018	4.9983	-0.0035
553	5e+12	NDD	4.9972	4.9784	-0.0188
554	5e+12	NDD	5.0076	4.9904	-0.0172
555	5e+12	NDD	5.0041	4.9871	-0.017
556	1e+13	NDD	4.9868	4.9534	-0.0334
557	1e+13	NDD	5.0195	4.9831	-0.0364
558	1e+13	NDD	5.0064	4.9717	-0.0347
559	0	NDD, Ctrl	4.9904	4.9904	0

Test Statistics (V)

Fluence(n/cm ²)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9904	4.9904	4.9904		4.9904	4.9904	4.9904		0	0	0	
1e+12	4.9845	4.9958	5.0018	0.0097654	4.9806	4.9922	4.9983	0.01005	-0.0039	-0.0035667	-0.0033	0.00030551
5e+12	4.9972	5.003	5.0076	0.0052918	4.9784	4.9853	4.9904	0.0061992	-0.0188	-0.017667	-0.017	0.00098658
1e+13	4.9868	5.0042	5.0195	0.016457	4.9534	4.9694	4.9831	0.014983	-0.0364	-0.034833	-0.0334	0.0015044

Device Test: 62.21 V_BP7L(V_BP7L IIM 5MHz VIN_14V)

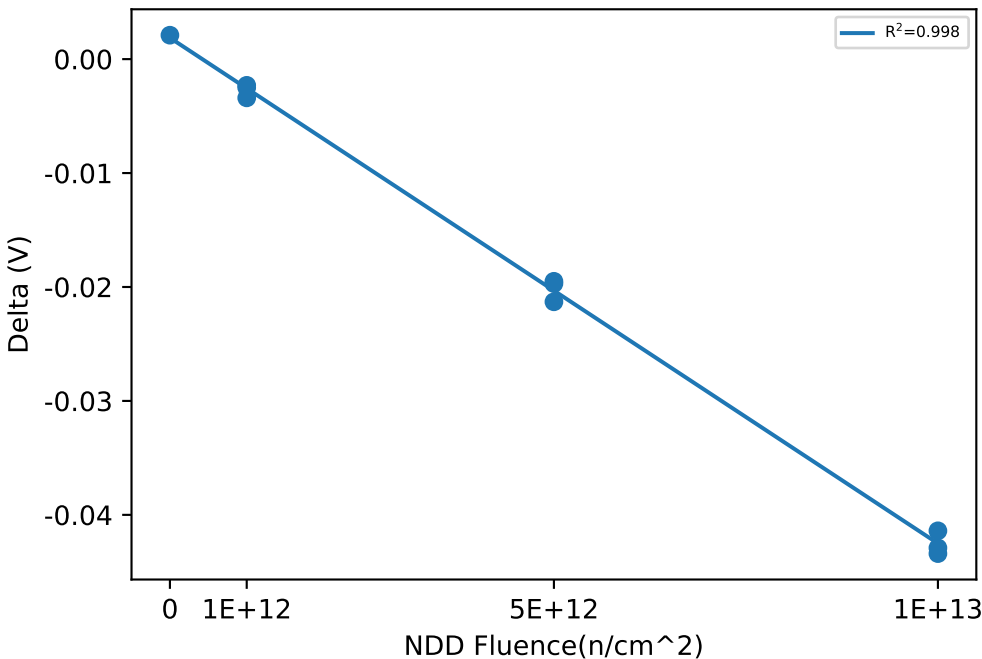
NDD vs Result Stats



Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	6.9801	6.9778	-0.0023
551	1e+12	NDD	6.9795	6.977	-0.0025
552	1e+12	NDD	7.0409	7.0375	-0.0034
553	5e+12	NDD	6.9878	6.9683	-0.0195
554	5e+12	NDD	6.9818	6.9605	-0.0213
555	5e+12	NDD	6.9673	6.9476	-0.0197
556	1e+13	NDD	7.0124	6.971	-0.0414
557	1e+13	NDD	7.0367	6.9938	-0.0429
558	1e+13	NDD	7.0191	6.9757	-0.0434
559	0	NDD, Ctrl	7.0003	7.0024	0.0021

NDD vs Post - Pre Exposure Delta

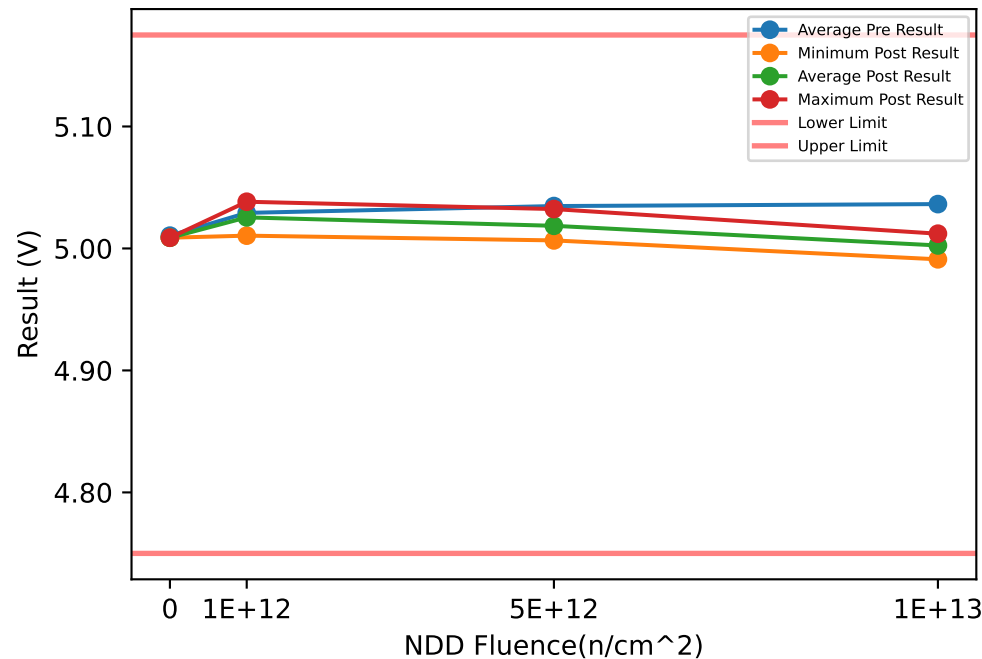


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0003	7.0003	7.0003		7.0024	7.0024	7.0024		0.0021	0.0021	0.0021	
1e+12	6.9795	7.0002	7.0409	0.035277	6.977	6.9974	7.0375	0.034701	-0.0034	-0.0027333	-0.0023	0.00058595
5e+12	6.9673	6.979	6.9878	0.01054	6.9476	6.9588	6.9683	0.010454	-0.0213	-0.020167	-0.0195	0.00098658
1e+13	7.0124	7.0227	7.0367	0.012551	6.971	6.9802	6.9938	0.012038	-0.0434	-0.042567	-0.0414	0.0010408

Device Test: 62.22 V_BP5L(V_BP5L IIM 5MHz VIN_14V)

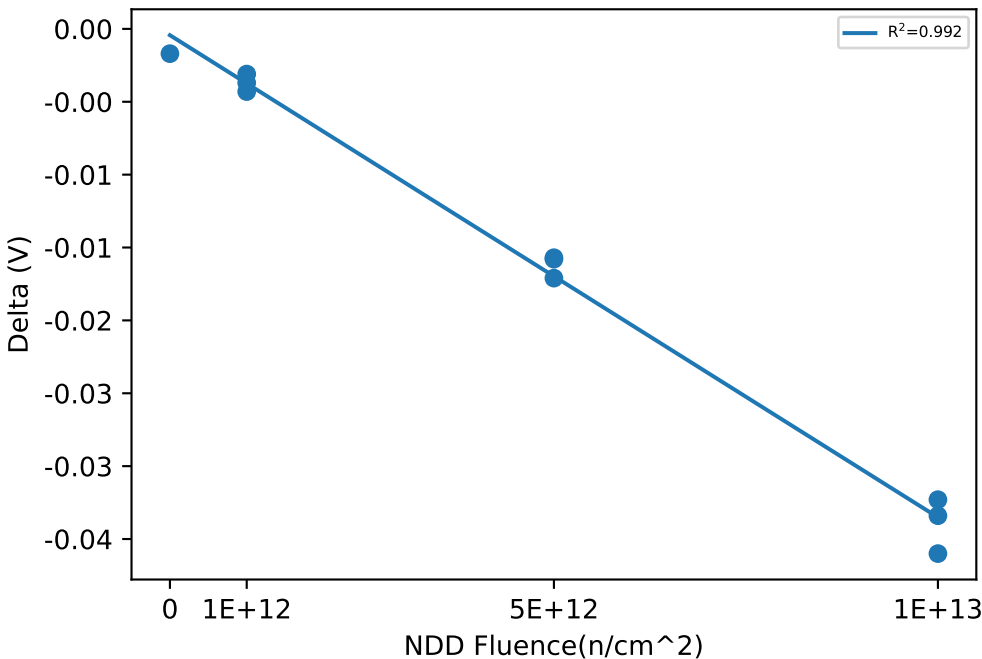
NDD vs Result Stats



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	5.0142	5.0105	-0.0037
551	1e+12	NDD	5.0319	5.0276	-0.0043
552	1e+12	NDD	5.0414	5.0383	-0.0031
553	5e+12	NDD	5.0326	5.0168	-0.0158
554	5e+12	NDD	5.0237	5.0066	-0.0171
555	5e+12	NDD	5.048	5.0323	-0.0157
556	1e+13	NDD	5.0245	4.9911	-0.0334
557	1e+13	NDD	5.0444	5.0121	-0.0323
558	1e+13	NDD	5.0402	5.0042	-0.036
559	0	NDD, Ctrl	5.0105	5.0088	-0.0017

NDD vs Post - Pre Exposure Delta

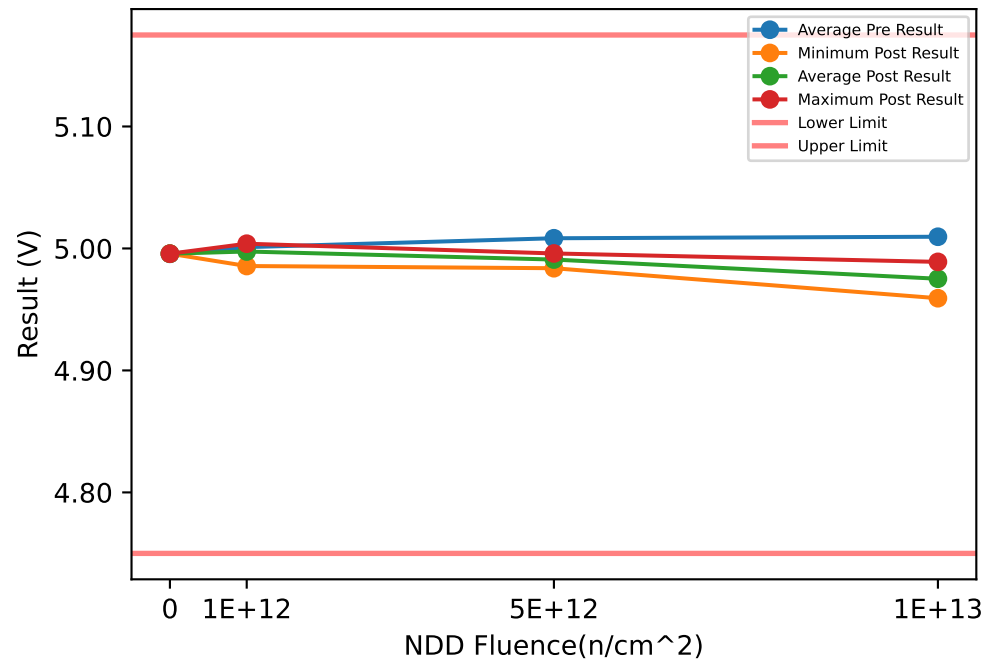


Test Statistics (V)

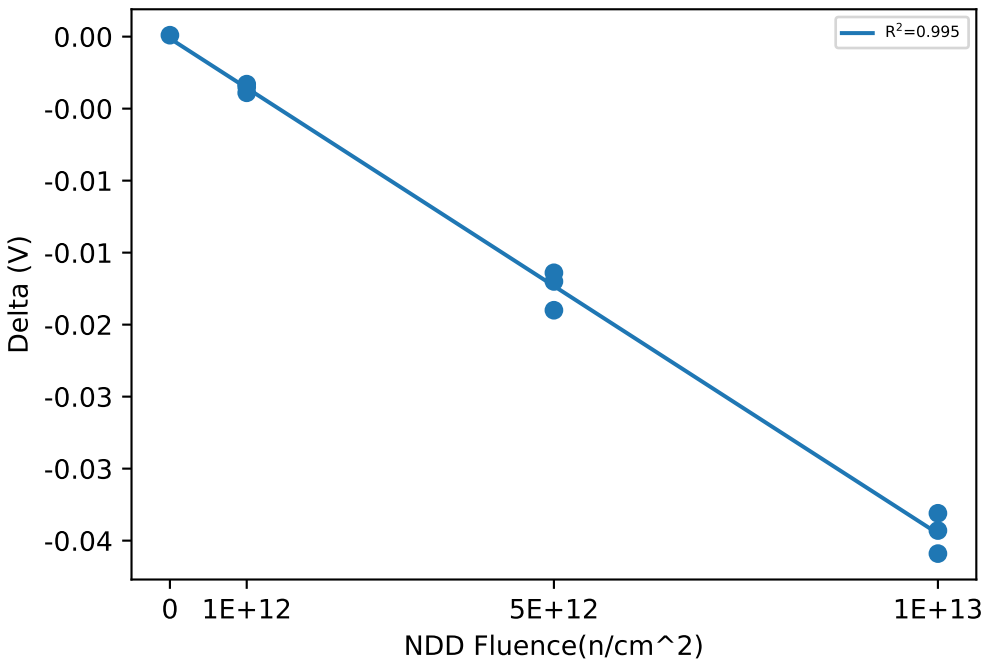
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0105	5.0105	5.0105		5.0088	5.0088	5.0088		-0.0017	-0.0017	-0.0017	
1e+12	5.0142	5.0292	5.0414	0.013804	5.0105	5.0255	5.0383	0.014022	-0.0043	-0.0037	-0.0031	0.0006
5e+12	5.0237	5.0348	5.048	0.012294	5.0066	5.0186	5.0323	0.012941	-0.0171	-0.0162	-0.0157	0.00078102
1e+13	5.0245	5.0364	5.0444	0.010489	4.9911	5.0025	5.0121	0.010607	-0.036	-0.0339	-0.0323	0.0019

Device Test: 62.23 V_BP5H(V_BP5H IIM 5MHz VIN_14V)

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

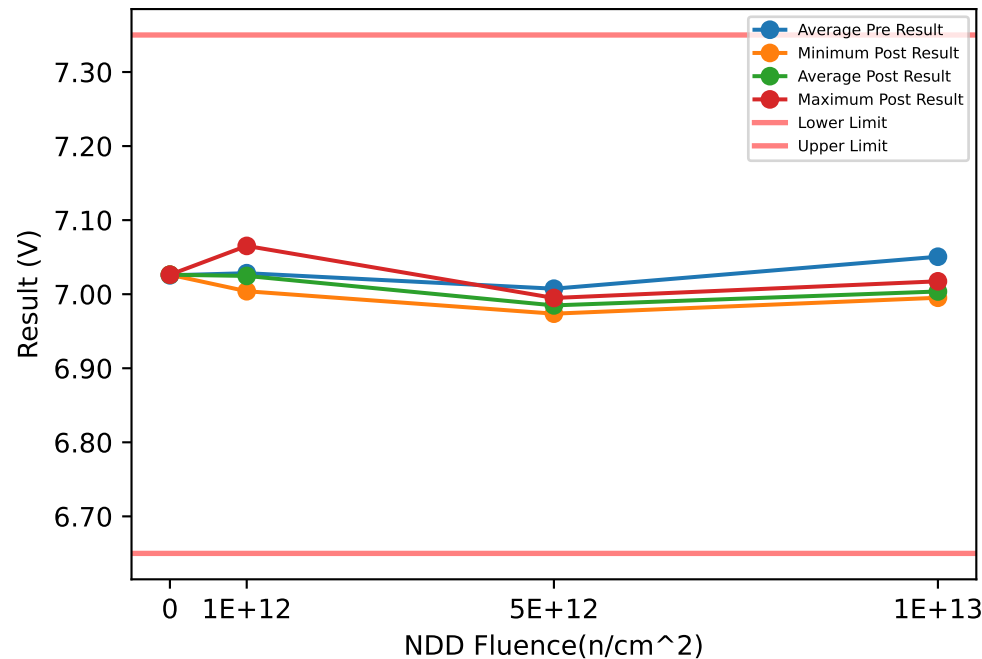
Serial #	Fluence(n/cm ²)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.9895	4.9856	-0.0039
551	1e+12	NDD	5.0065	5.003	-0.0035
552	1e+12	NDD	5.0072	5.0039	-0.0033
553	5e+12	NDD	5.0028	4.9838	-0.019
554	5e+12	NDD	5.0129	4.9959	-0.017
555	5e+12	NDD	5.0094	4.993	-0.0164
556	1e+13	NDD	4.9923	4.9592	-0.0331
557	1e+13	NDD	5.0249	4.989	-0.0359
558	1e+13	NDD	5.0116	4.9773	-0.0343
559	0	NDD, Ctrl	4.9956	4.9957	0.0001

Test Statistics (V)

Fluence(n/cm ²)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9956	4.9956	4.9956		4.9957	4.9957	4.9957		0.0001	0.0001	0.0001	
1e+12	4.9895	5.0011	5.0072	0.010023	4.9856	4.9975	5.0039	0.010316	-0.0039	-0.0035667	-0.0033	0.00030551
5e+12	5.0028	5.0084	5.0129	0.0051287	4.9838	4.9909	4.9959	0.0063174	-0.019	-0.017467	-0.0164	0.0013614
1e+13	4.9923	5.0096	5.0249	0.016392	4.9592	4.9752	4.989	0.015014	-0.0359	-0.034433	-0.0331	0.0014048

Device Test: 62.3 V_BP7L(V_BP7L PWM 1MHz VIN_14V)

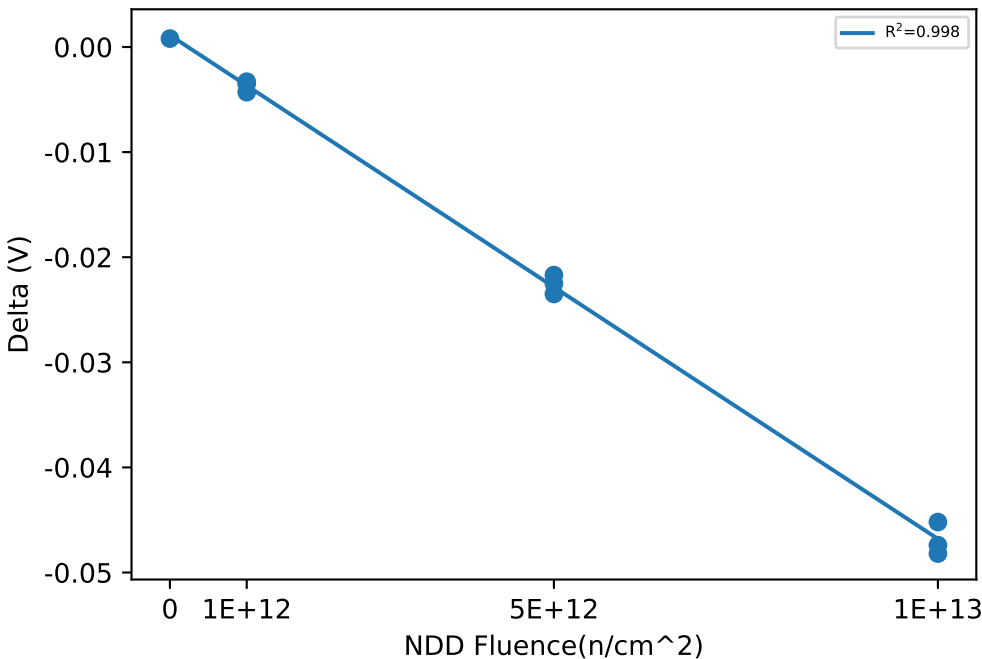
NDD vs Result Stats



Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	7.0073	7.004	-0.0033
551	1e+12	NDD	7.0083	7.0048	-0.0035
552	1e+12	NDD	7.0695	7.0652	-0.0043
553	5e+12	NDD	7.0166	6.9949	-0.0217
554	5e+12	NDD	7.0095	6.986	-0.0235
555	5e+12	NDD	6.9962	6.9737	-0.0225
556	1e+13	NDD	7.0404	6.9952	-0.0452
557	1e+13	NDD	7.0648	7.0174	-0.0474
558	1e+13	NDD	7.0466	6.9984	-0.0482
559	0	NDD, Ctrl	7.0255	7.0263	0.0008

NDD vs Post - Pre Exposure Delta

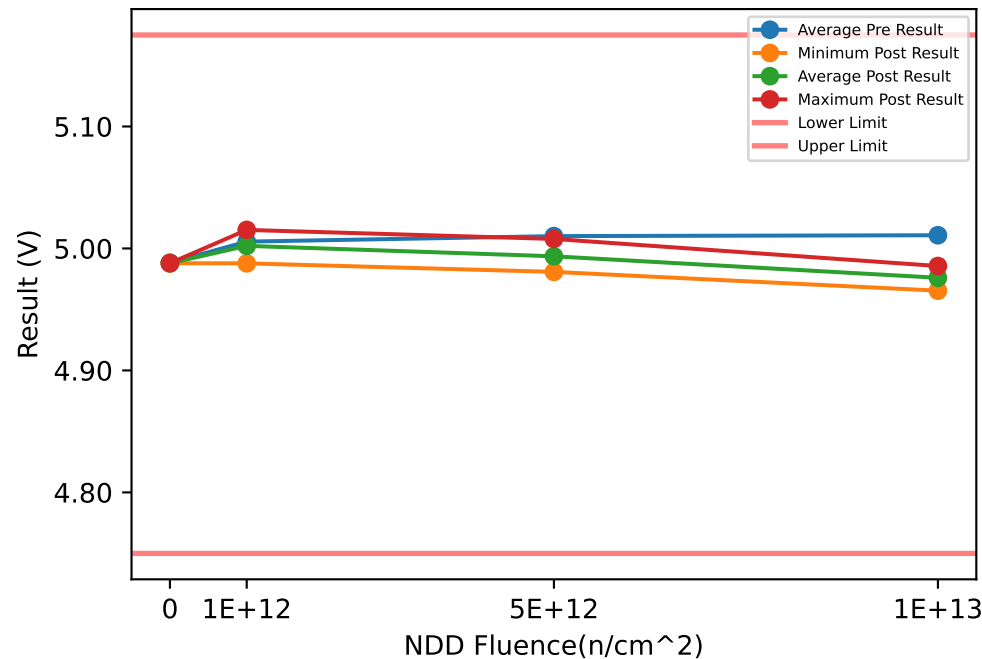


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0255	7.0255	7.0255		7.0263	7.0263	7.0263		0.0008	0.0008	0.0008	
1e+12	7.0073	7.0284	7.0695	0.035626	7.004	7.0247	7.0652	0.035105	-0.0043	-0.0037	-0.0033	0.00052915
5e+12	6.9962	7.0074	7.0166	0.010356	6.9737	6.9849	6.9949	0.010645	-0.0235	-0.022567	-0.0217	0.00090185
1e+13	7.0404	7.0506	7.0648	0.012682	6.9952	7.0037	7.0174	0.012001	-0.0482	-0.046933	-0.0452	0.0015535

Device Test: 62.4 V_BP5L(V_BP5L PWM 1MHz VIN_14V)

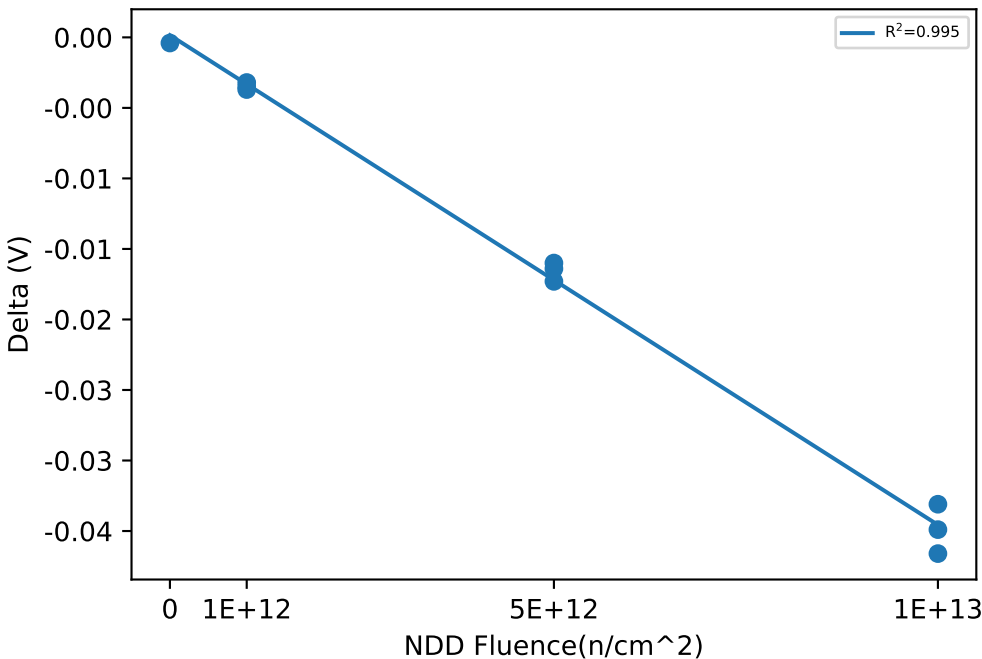
NDD vs Result Stats



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.9913	4.9878	-0.0035
551	1e+12	NDD	5.0071	5.0034	-0.0037
552	1e+12	NDD	5.0184	5.0152	-0.0032
553	5e+12	NDD	5.0081	4.9921	-0.016
554	5e+12	NDD	4.9981	4.9808	-0.0173
555	5e+12	NDD	5.0242	5.0078	-0.0164
556	1e+13	NDD	5.0003	4.9654	-0.0349
557	1e+13	NDD	5.0187	4.9856	-0.0331
558	1e+13	NDD	5.0135	4.9769	-0.0366
559	0	NDD, Ctrl	4.9883	4.9879	-0.0004

NDD vs Post - Pre Exposure Delta

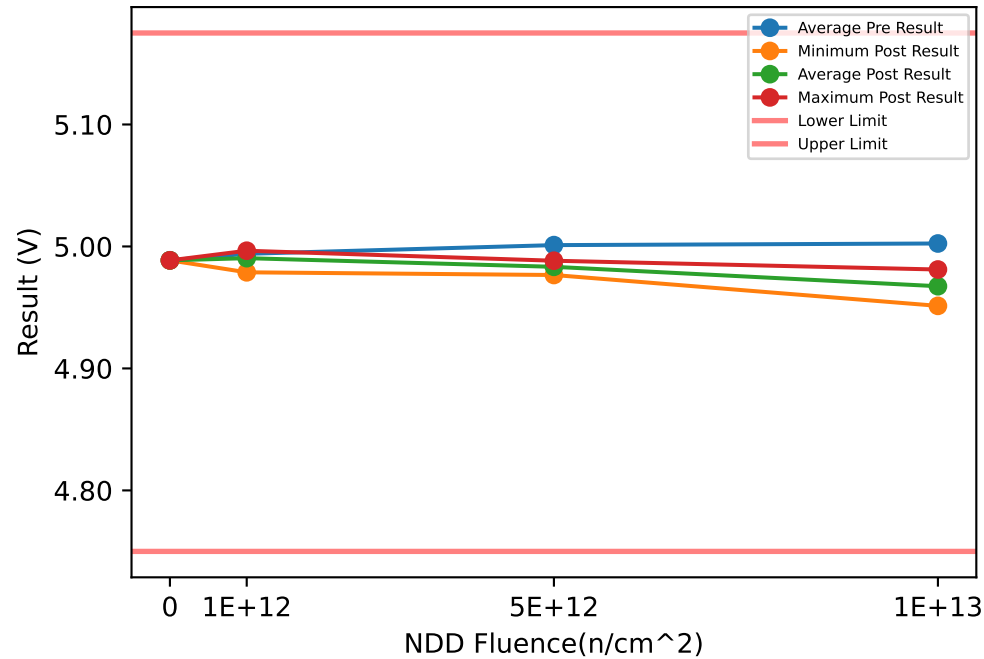


Test Statistics (V)

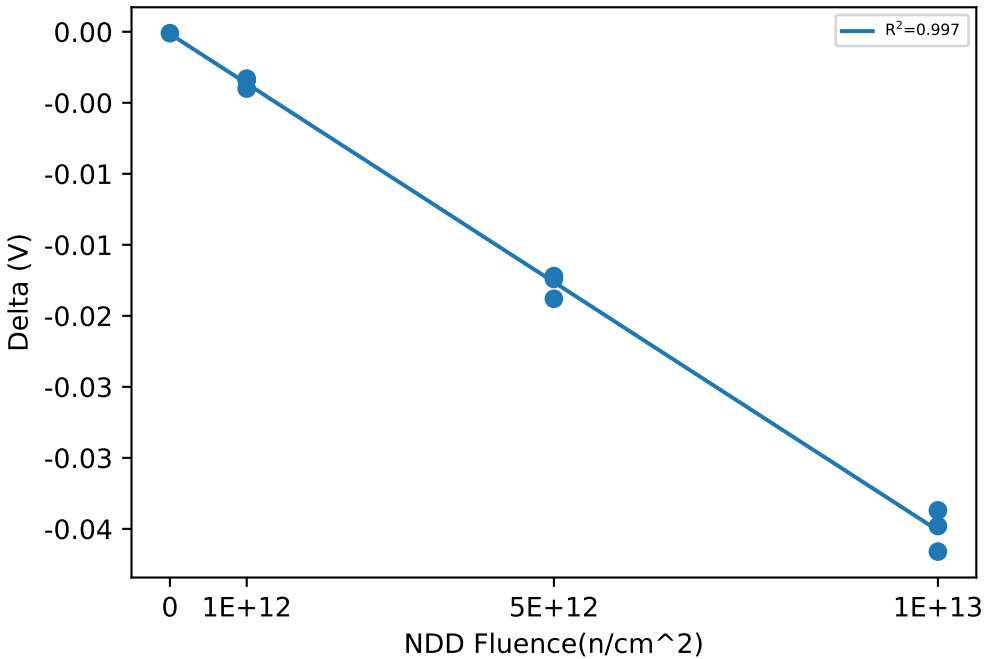
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9883	4.9883	4.9883		4.9879	4.9879	4.9879		-0.0004	-0.0004	-0.0004	
1e+12	4.9913	5.0056	5.0184	0.013612	4.9878	5.0021	5.0152	0.013744	-0.0037	-0.0034667	-0.0032	0.00025166
5e+12	4.9981	5.0101	5.0242	0.013168	4.9808	4.9936	5.0078	0.01356	-0.0173	-0.016567	-0.016	0.00066583
1e+13	5.0003	5.0108	5.0187	0.0094854	4.9654	4.976	4.9856	0.010132	-0.0366	-0.034867	-0.0331	0.0017502

Device Test: 62.5 V_BP5H(V_BP5H PWM 1MHz VIN_14V)

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

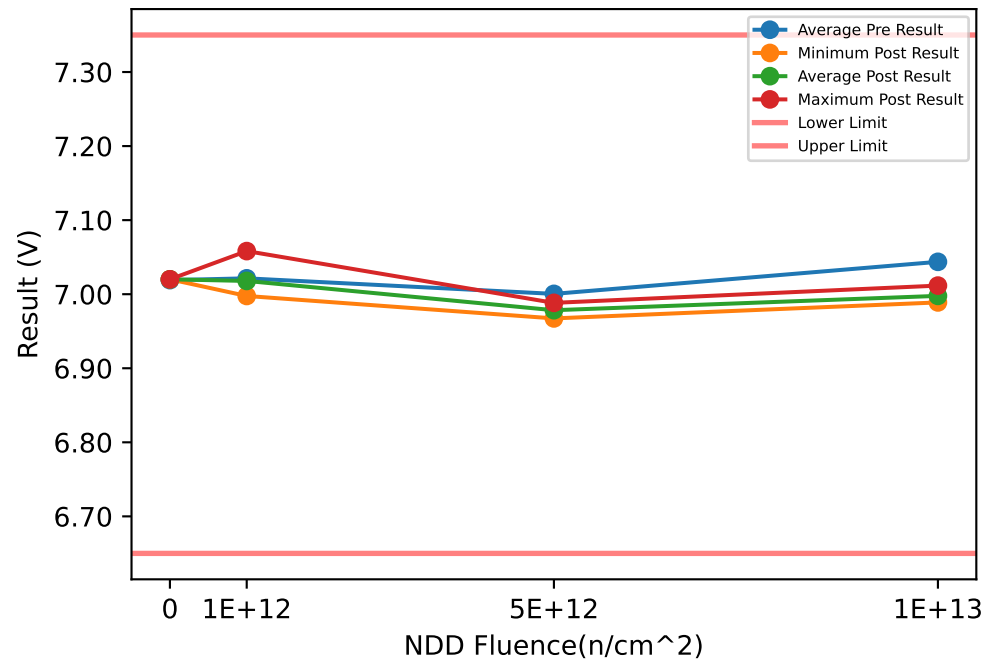
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.9828	4.9788	-0.004
551	1e+12	NDD	4.9992	4.9959	-0.0033
552	1e+12	NDD	4.9999	4.9965	-0.0034
553	5e+12	NDD	4.9954	4.9766	-0.0188
554	5e+12	NDD	5.0057	4.9883	-0.0174
555	5e+12	NDD	5.0022	4.985	-0.0172
556	1e+13	NDD	4.985	4.9513	-0.0337
557	1e+13	NDD	5.0177	4.9811	-0.0366
558	1e+13	NDD	5.0046	4.9698	-0.0348
559	0	NDD, Ctrl	4.9887	4.9886	-0.0001

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9887	4.9887	4.9887		4.9886	4.9886	4.9886		-0.0001	-0.0001	-0.0001	
1e+12	4.9828	4.994	4.9999	0.0096769	4.9788	4.9904	4.9965	0.01005	-0.004	-0.0035667	-0.0033	0.00037859
5e+12	4.9954	5.0011	5.0057	0.0052374	4.9766	4.9833	4.9883	0.0060324	-0.0188	-0.0178	-0.0172	0.00087178
1e+13	4.985	5.0024	5.0177	0.016457	4.9513	4.9674	4.9811	0.015044	-0.0366	-0.035033	-0.0337	0.001464

Device Test: 62.6 V_BP7L(V_BP7L PWM 2MHz VIN_14V)

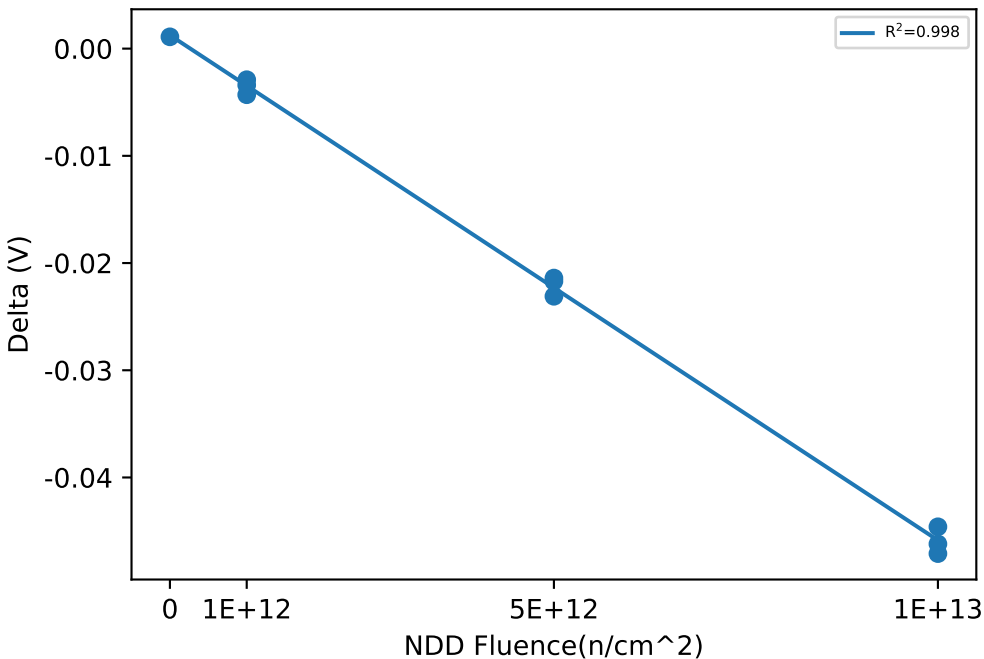
NDD vs Result Stats



Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	7.0005	6.9976	-0.0029
551	1e+12	NDD	7.0013	6.9979	-0.0034
552	1e+12	NDD	7.0625	7.0582	-0.0043
553	5e+12	NDD	7.0097	6.9883	-0.0214
554	5e+12	NDD	7.0026	6.9795	-0.0231
555	5e+12	NDD	6.989	6.9673	-0.0217
556	1e+13	NDD	7.0335	6.9889	-0.0446
557	1e+13	NDD	7.0578	7.0116	-0.0462
558	1e+13	NDD	7.0398	6.9927	-0.0471
559	0	NDD, Ctrl	7.019	7.0201	0.0011

NDD vs Post - Pre Exposure Delta

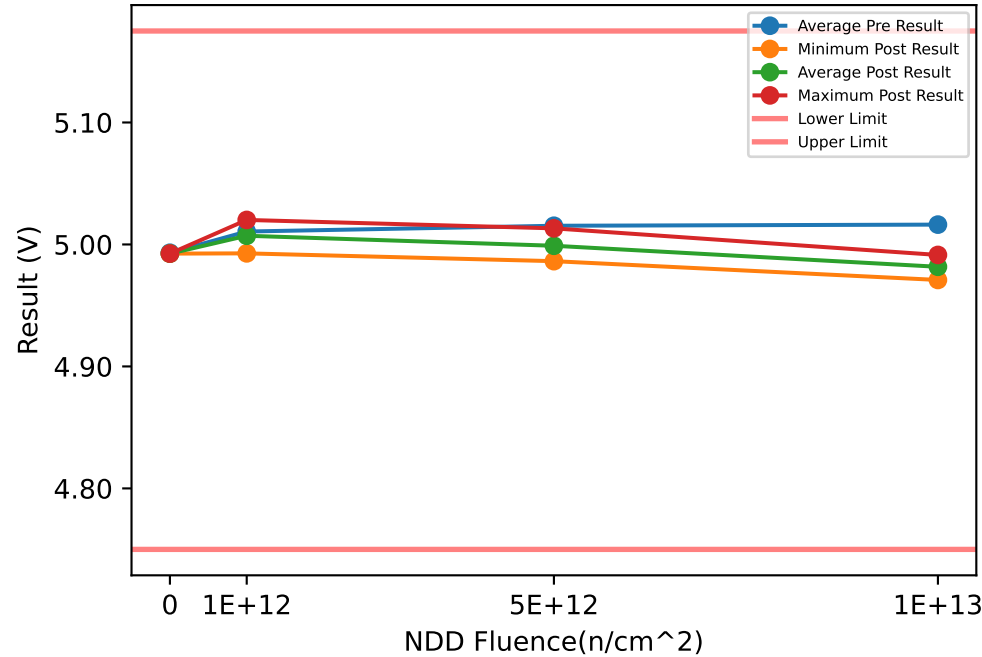


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.019	7.019	7.019		7.0201	7.0201	7.0201		0.0011	0.0011	0.0011	
1e+12	7.0005	7.0214	7.0625	0.035567	6.9976	7.0179	7.0582	0.034901	-0.0043	-0.0035333	-0.0029	0.00070946
5e+12	6.989	7.0004	7.0097	0.010519	6.9673	6.9784	6.9883	0.010546	-0.0231	-0.022067	-0.0214	0.00090738
1e+13	7.0335	7.0437	7.0578	0.012611	6.9889	6.9977	7.0116	0.012158	-0.0471	-0.045967	-0.0446	0.0012662

Device Test: 62.7 V_BP5L(V_BP5L PWM 2MHz VIN_14V)

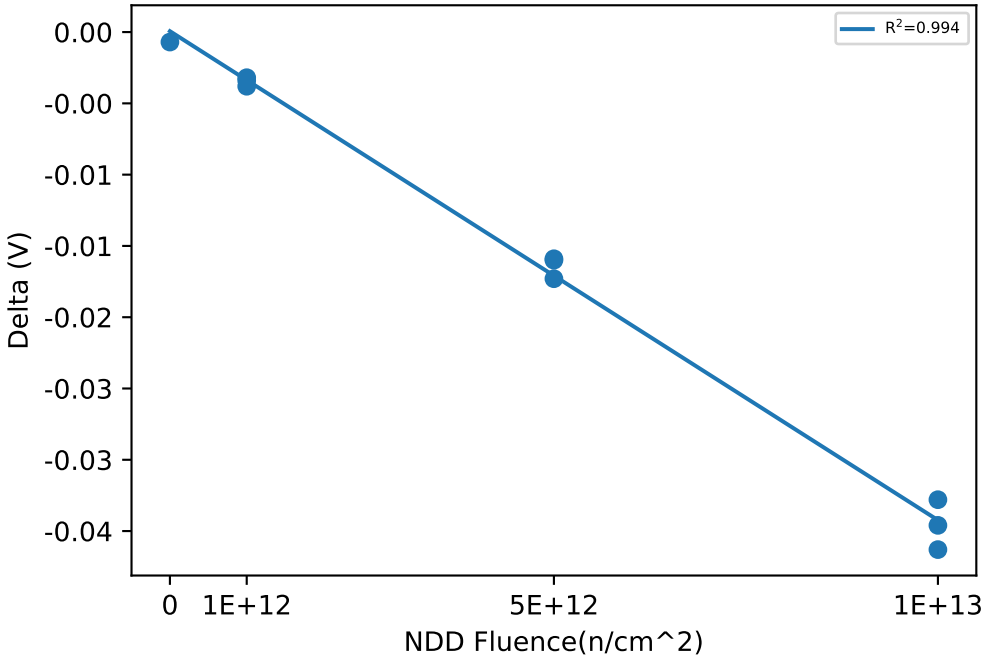
NDD vs Result Stats



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.9961	4.9927	-0.0034
551	1e+12	NDD	5.0124	5.0086	-0.0038
552	1e+12	NDD	5.0233	5.0201	-0.0032
553	5e+12	NDD	5.0132	4.9973	-0.0159
554	5e+12	NDD	5.0036	4.9863	-0.0173
555	5e+12	NDD	5.0292	5.0132	-0.016
556	1e+13	NDD	5.0055	4.9709	-0.0346
557	1e+13	NDD	5.0242	4.9914	-0.0328
558	1e+13	NDD	5.0191	4.9828	-0.0363
559	0	NDD, Ctrl	4.9932	4.9925	-0.0007

NDD vs Post - Pre Exposure Delta

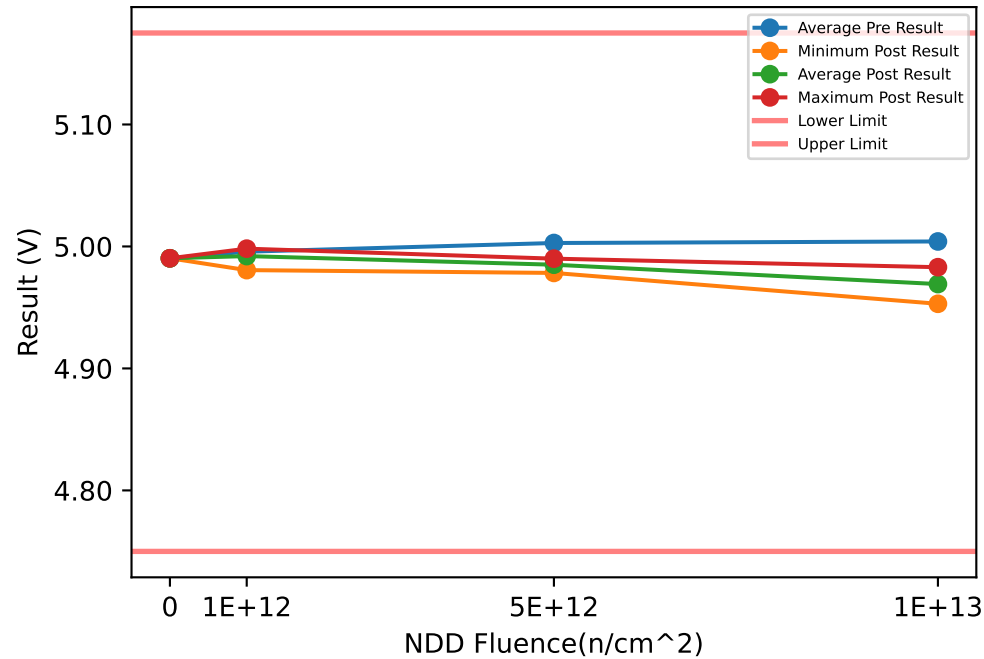


Test Statistics (V)

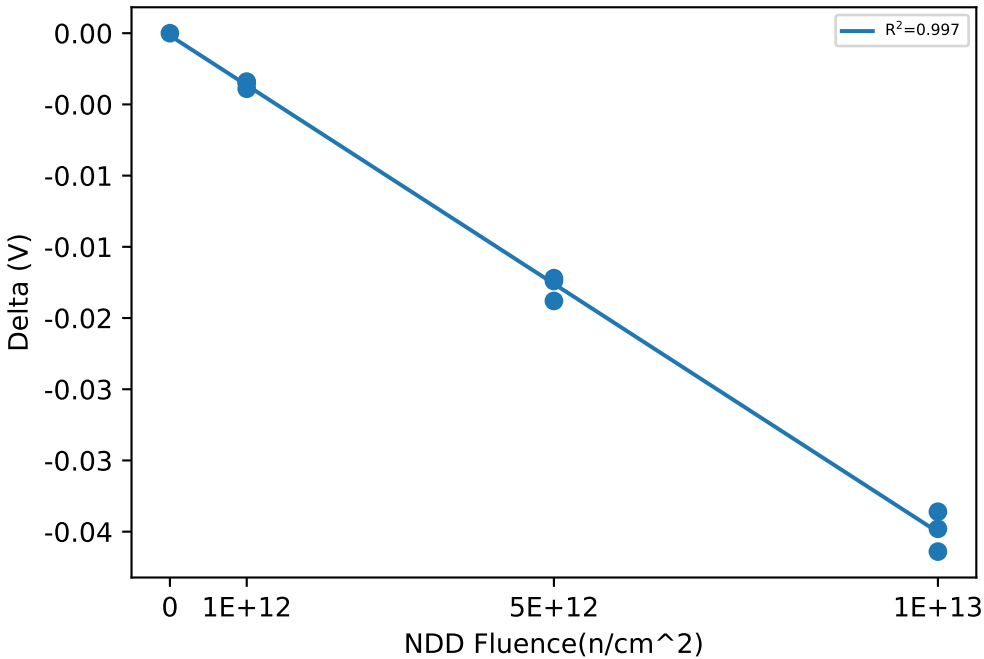
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9932	4.9932	4.9932		4.9925	4.9925	4.9925		-0.0007	-0.0007	-0.0007	
1e+12	4.9961	5.0106	5.0233	0.013689	4.9927	5.0071	5.0201	0.013759	-0.0038	-0.0034667	-0.0032	0.00030551
5e+12	5.0036	5.0153	5.0292	0.012933	4.9863	4.9989	5.0132	0.013524	-0.0173	-0.0164	-0.0159	0.00078102
1e+13	5.0055	5.0163	5.0242	0.0096666	4.9709	4.9817	4.9914	0.010294	-0.0363	-0.034567	-0.0328	0.0017502

Device Test: 62.8 V_BP5H(V_BP5H PWM 2MHz VIN_14V)

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 4.75, Upper Limit = 5.175 (V))

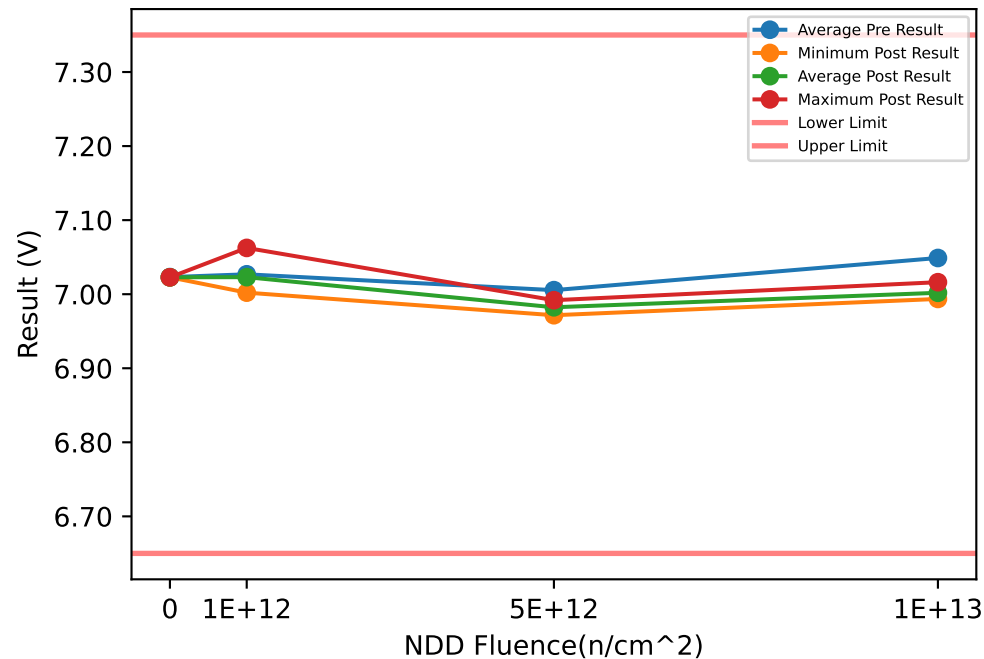
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.9845	4.9806	-0.0039
551	1e+12	NDD	5.0009	4.9975	-0.0034
552	1e+12	NDD	5.0017	4.9982	-0.0035
553	5e+12	NDD	4.9971	4.9783	-0.0188
554	5e+12	NDD	5.0074	4.99	-0.0174
555	5e+12	NDD	5.004	4.9868	-0.0172
556	1e+13	NDD	4.9866	4.953	-0.0336
557	1e+13	NDD	5.0194	4.983	-0.0364
558	1e+13	NDD	5.0063	4.9715	-0.0348
559	0	NDD, Ctrl	4.9903	4.9903	0

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9903	4.9903	4.9903		4.9903	4.9903	4.9903		0	0	0	
1e+12	4.9845	4.9957	5.0017	0.0097077	4.9806	4.9921	4.9982	0.0099654	-0.0039	-0.0036	-0.0034	0.00026458
5e+12	4.9971	5.0028	5.0074	0.0052482	4.9783	4.985	4.99	0.0060468	-0.0188	-0.0178	-0.0172	0.00087178
1e+13	4.9866	5.0041	5.0194	0.01651	4.953	4.9692	4.983	0.015135	-0.0364	-0.034933	-0.0336	0.0014048

Device Test: 62.9 V_BP7L(V_BP7L PWM 5MHz VIN_14V)

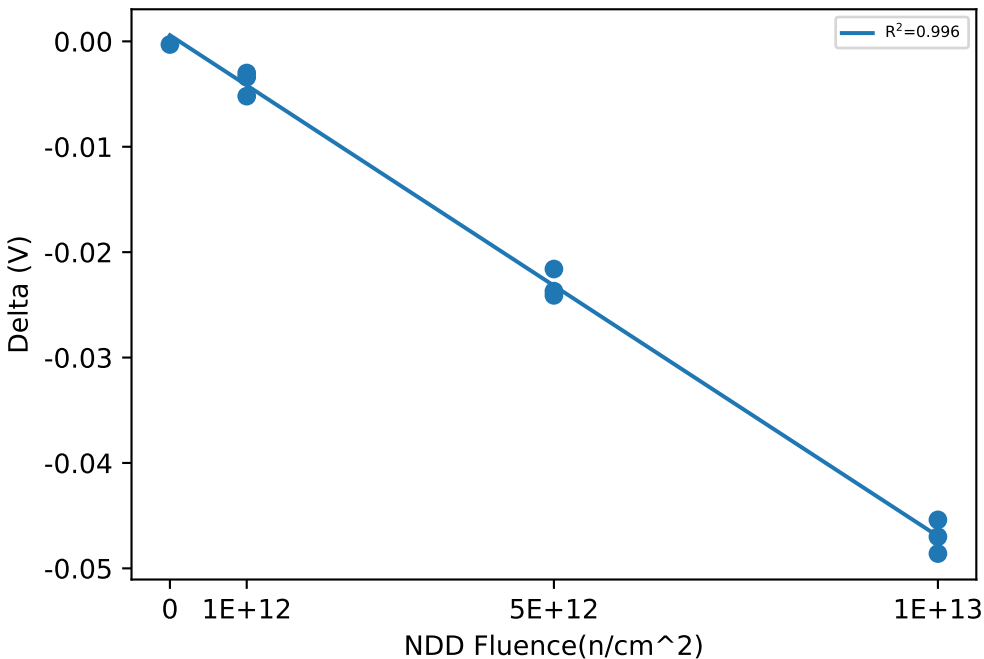
NDD vs Result Stats



Test Results (Lower Limit = 6.65, Upper Limit = 7.35 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	7.0055	7.0021	-0.0034
551	1e+12	NDD	7.0074	7.0044	-0.003
552	1e+12	NDD	7.0677	7.0625	-0.0052
553	5e+12	NDD	7.0135	6.9919	-0.0216
554	5e+12	NDD	7.0076	6.9835	-0.0241
555	5e+12	NDD	6.9953	6.9716	-0.0237
556	1e+13	NDD	7.039	6.9936	-0.0454
557	1e+13	NDD	7.0632	7.0162	-0.047
558	1e+13	NDD	7.0445	6.9959	-0.0486
559	0	NDD, Ctrl	7.0231	7.0228	-0.0003

NDD vs Post - Pre Exposure Delta

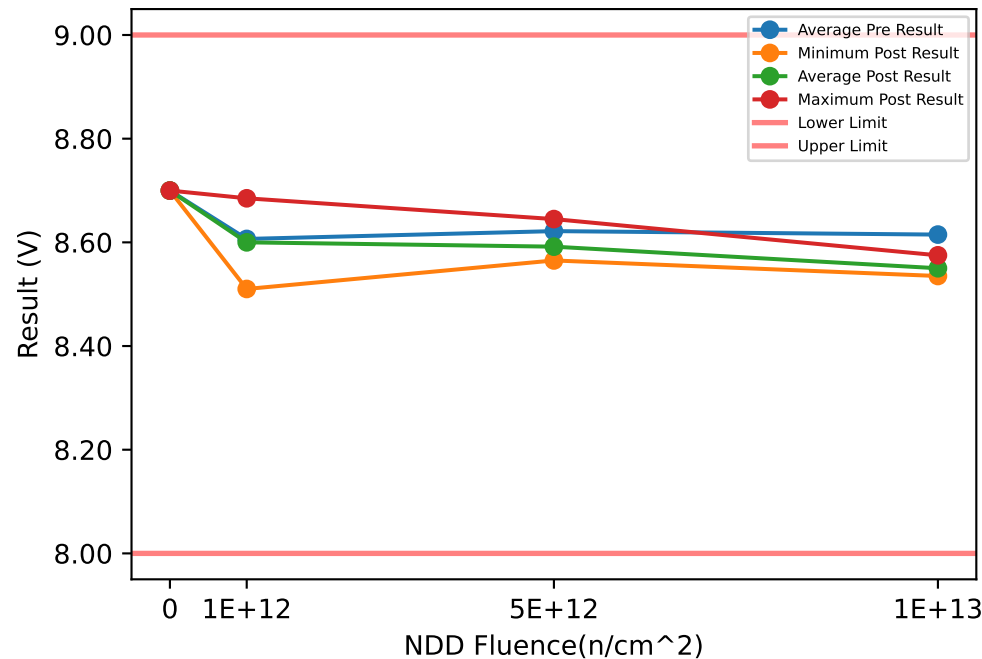


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0231	7.0231	7.0231		7.0228	7.0228	7.0228		-0.0003	-0.0003	-0.0003	
1e+12	7.0055	7.0269	7.0677	0.035375	7.0021	7.023	7.0625	0.034227	-0.0052	-0.0038667	-0.003	0.0011719
5e+12	6.9953	7.0055	7.0135	0.0092857	6.9716	6.9823	6.9919	0.0102	-0.0241	-0.023133	-0.0216	0.0013429
1e+13	7.039	7.0489	7.0632	0.012686	6.9936	7.0019	7.0162	0.012437	-0.0486	-0.047	-0.0454	0.0016

Device Test: 70.0 V_IN_TH_RISE(UVLO VIN Rise Thresh)

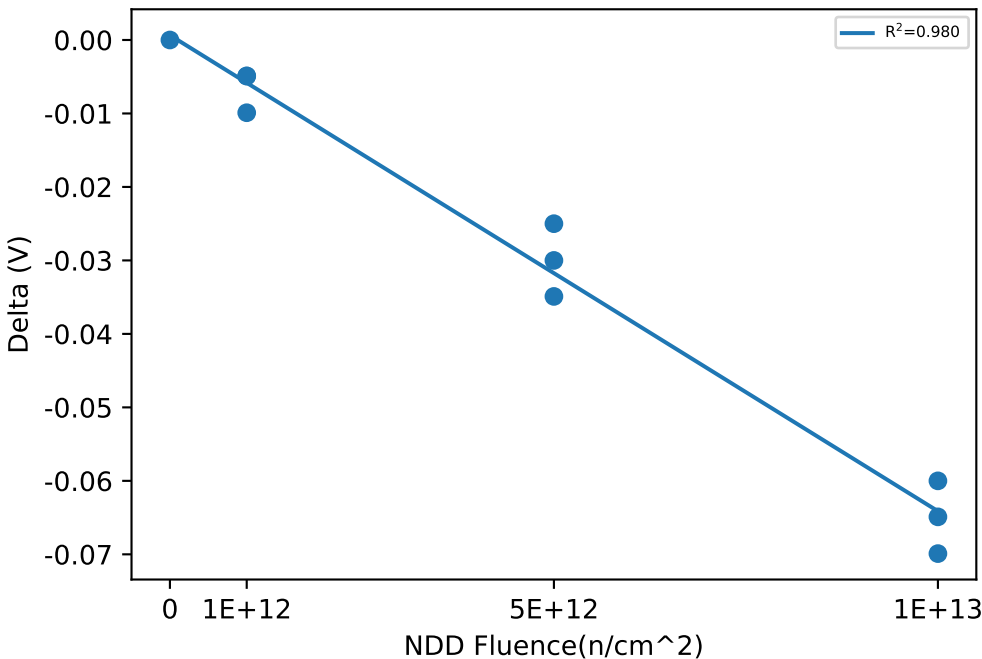
NDD vs Result Stats



Test Results (Lower Limit = 8.0, Upper Limit = 9.0 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	8.6949	8.685	-0.0099
551	1e+12	NDD	8.515	8.5101	-0.0049
552	1e+12	NDD	8.6099	8.605	-0.0049
553	5e+12	NDD	8.6699	8.6449	-0.025
554	5e+12	NDD	8.5951	8.5651	-0.03
555	5e+12	NDD	8.6	8.5651	-0.0349
556	1e+13	NDD	8.605	8.5351	-0.0699
557	1e+13	NDD	8.635	8.575	-0.06
558	1e+13	NDD	8.605	8.5401	-0.0649
559	0	NDD, Ctrl	8.6999	8.6999	0

NDD vs Post - Pre Exposure Delta

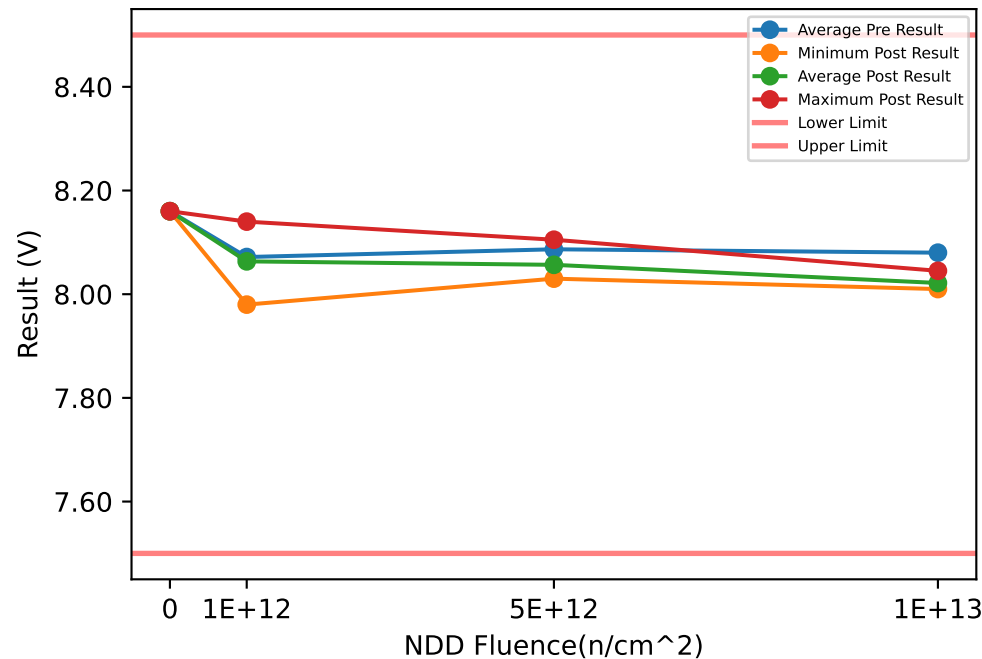


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.6999	8.6999	8.6999		8.6999	8.6999	8.6999		0	0	0	
1e+12	8.515	8.6066	8.6949	0.089995	8.5101	8.6	8.685	0.087556	-0.0099	-0.0065667	-0.0049	0.0028868
5e+12	8.5951	8.6217	8.6699	0.041843	8.5651	8.5917	8.6449	0.046073	-0.0349	-0.029967	-0.025	0.0049501
1e+13	8.605	8.615	8.635	0.017321	8.5351	8.5501	8.575	0.021737	-0.0699	-0.064933	-0.06	0.0049501

Device Test: 70.1 V_IN_TH_FALL(UVLO VIN Fall Thresh)

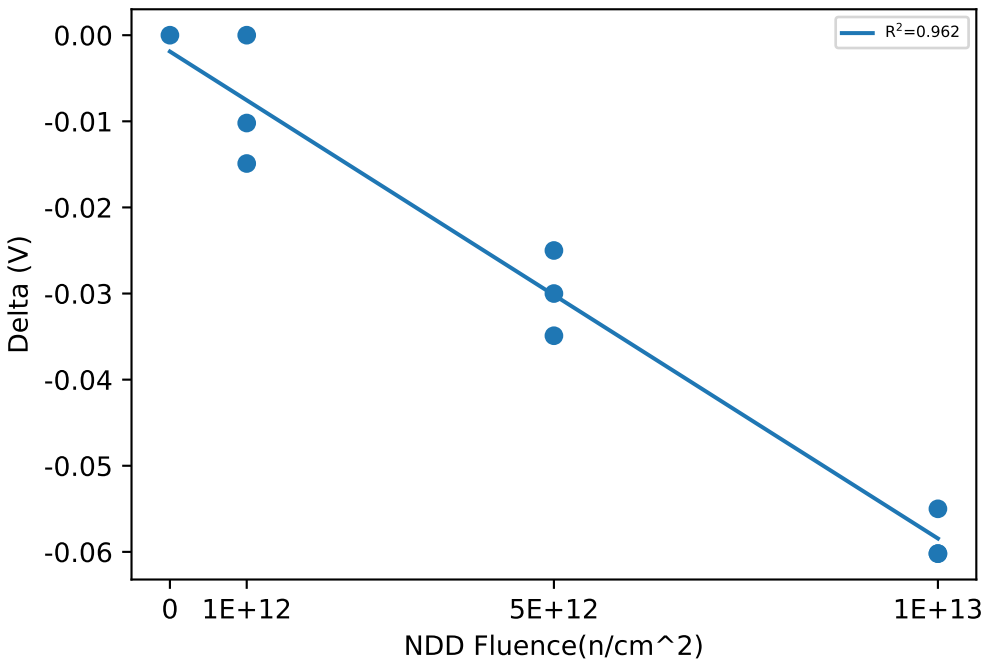
NDD vs Result Stats



Test Results (Lower Limit = 7.5, Upper Limit = 8.5 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	8.1549	8.14	-0.0149
551	1e+12	NDD	7.9901	7.9799	-0.0102
552	1e+12	NDD	8.0701	8.0701	0
553	5e+12	NDD	8.1351	8.1051	-0.03
554	5e+12	NDD	8.0599	8.0349	-0.025
555	5e+12	NDD	8.0649	8.03	-0.0349
556	1e+13	NDD	8.0701	8.0099	-0.0602
557	1e+13	NDD	8.1001	8.0451	-0.055
558	1e+13	NDD	8.0701	8.0099	-0.0602
559	0	NDD, Ctrl	8.1601	8.1601	0

NDD vs Post - Pre Exposure Delta

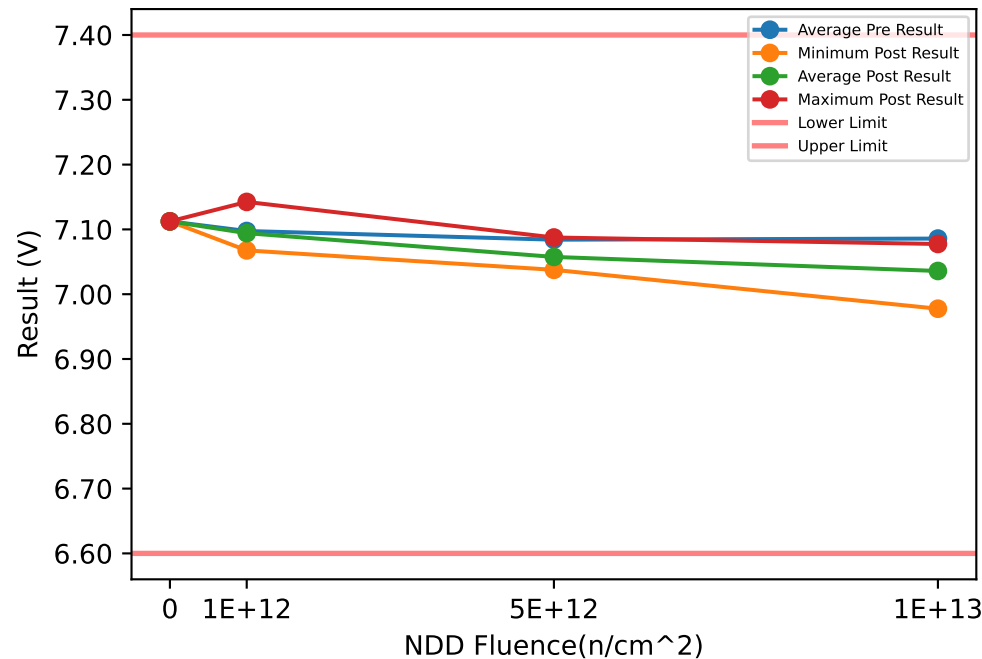


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.1601	8.1601	8.1601		8.1601	8.1601	8.1601		0	0	0	
1e+12	7.9901	8.0717	8.1549	0.082412	7.9799	8.0633	8.14	0.080264	-0.0149	-0.0083667	0	0.0076173
5e+12	8.0599	8.0866	8.1351	0.042048	8.03	8.0567	8.1051	0.042016	-0.0349	-0.029967	-0.025	0.0049501
1e+13	8.0701	8.0801	8.1001	0.017321	8.0099	8.0216	8.0451	0.020323	-0.0602	-0.058467	-0.055	0.0030022

Device Test: 75.0 V_BOOT_TH_RISE(UVLO BOOT Rise Thresh)

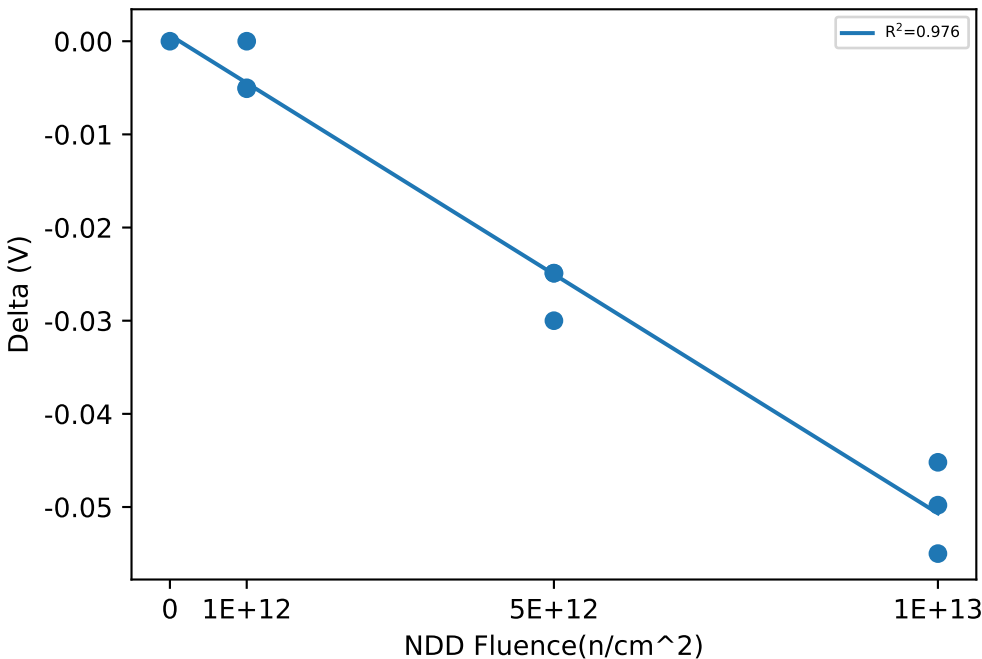
NDD vs Result Stats



Test Results (Lower Limit = 6.6, Upper Limit = 7.4 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	7.0775	7.0725	-0.005
551	1e+12	NDD	7.0676	7.0676	0
552	1e+12	NDD	7.1475	7.1424	-0.0051
553	5e+12	NDD	7.0625	7.0376	-0.0249
554	5e+12	NDD	7.0775	7.0475	-0.03
555	5e+12	NDD	7.1124	7.0875	-0.0249
556	1e+13	NDD	7.0274	6.9776	-0.0498
557	1e+13	NDD	7.0976	7.0524	-0.0452
558	1e+13	NDD	7.1325	7.0775	-0.055
559	0	NDD, Ctrl	7.1124	7.1124	0

NDD vs Post - Pre Exposure Delta

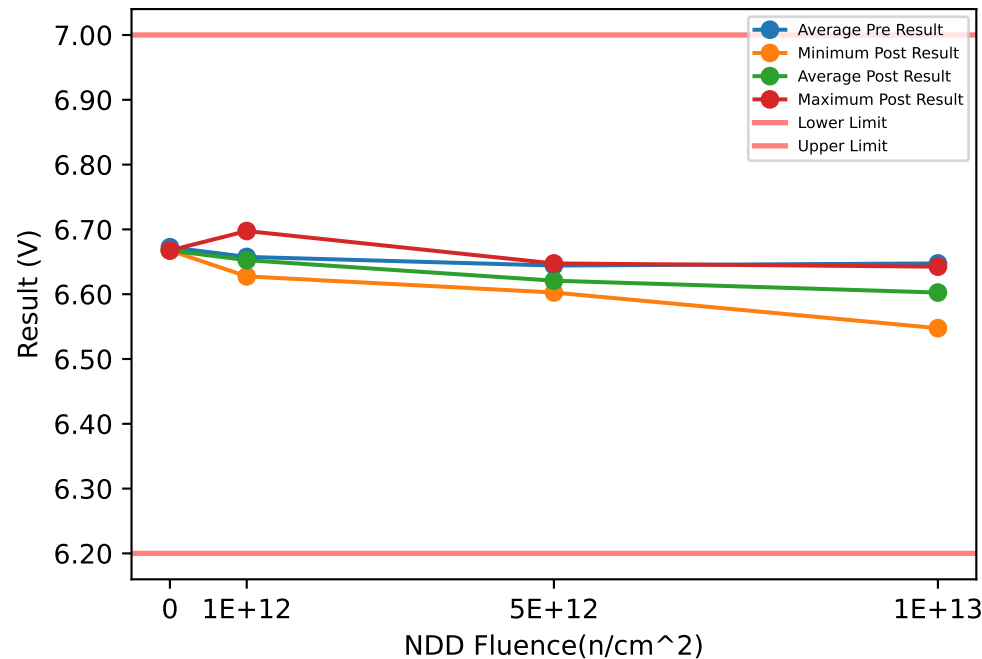


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.1124	7.1124	7.1124		7.1124	7.1124	7.1124		0	0	0	
1e+12	7.0676	7.0975	7.1475	0.043555	7.0676	7.0942	7.1424	0.041843	-0.0051	-0.0033667	0	0.002916
5e+12	7.0625	7.0841	7.1124	0.025603	7.0376	7.0575	7.0875	0.02642	-0.03	-0.0266	-0.0249	0.0029445
1e+13	7.0274	7.0858	7.1325	0.053529	6.9776	7.0358	7.0775	0.05197	-0.055	-0.05	-0.0452	0.0049031

Device Test: 75.1 V_BOOT_TH_FALL(UVLO BOOT Fall Thresh)

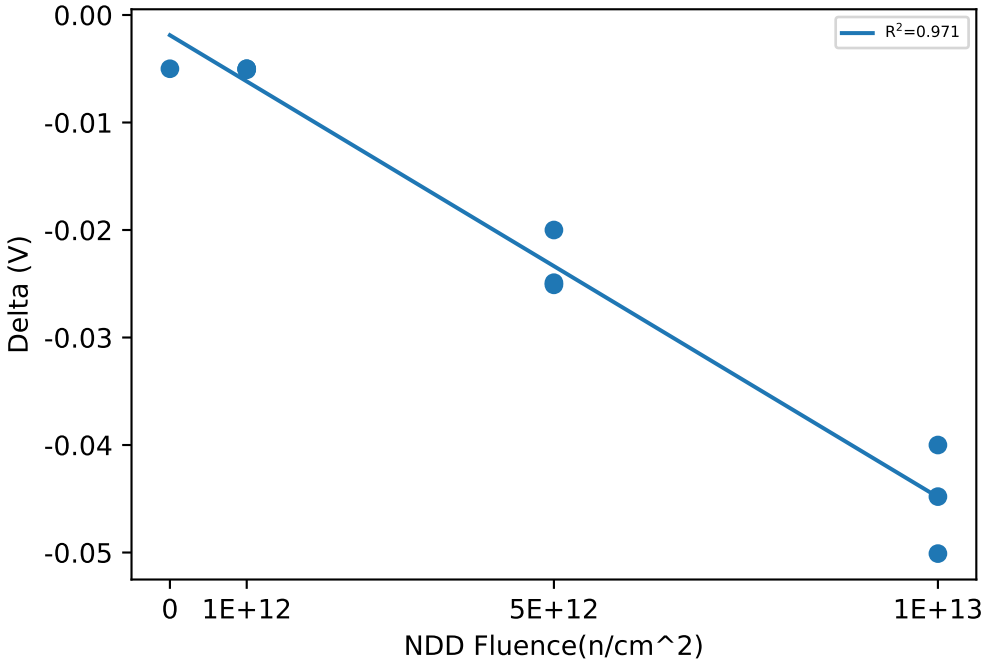
NDD vs Result Stats



Test Results (Lower Limit = 6.2, Upper Limit = 7.0 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	6.6376	6.6326	-0.005
551	1e+12	NDD	6.6326	6.6275	-0.0051
552	1e+12	NDD	6.7025	6.6975	-0.005
553	5e+12	NDD	6.6275	6.6026	-0.0249
554	5e+12	NDD	6.6376	6.6125	-0.0251
555	5e+12	NDD	6.6675	6.6475	-0.02
556	1e+13	NDD	6.5924	6.5476	-0.0448
557	1e+13	NDD	6.6575	6.6175	-0.04
558	1e+13	NDD	6.6926	6.6425	-0.0501
559	0	NDD, Ctrl	6.6725	6.6675	-0.005

NDD vs Post - Pre Exposure Delta

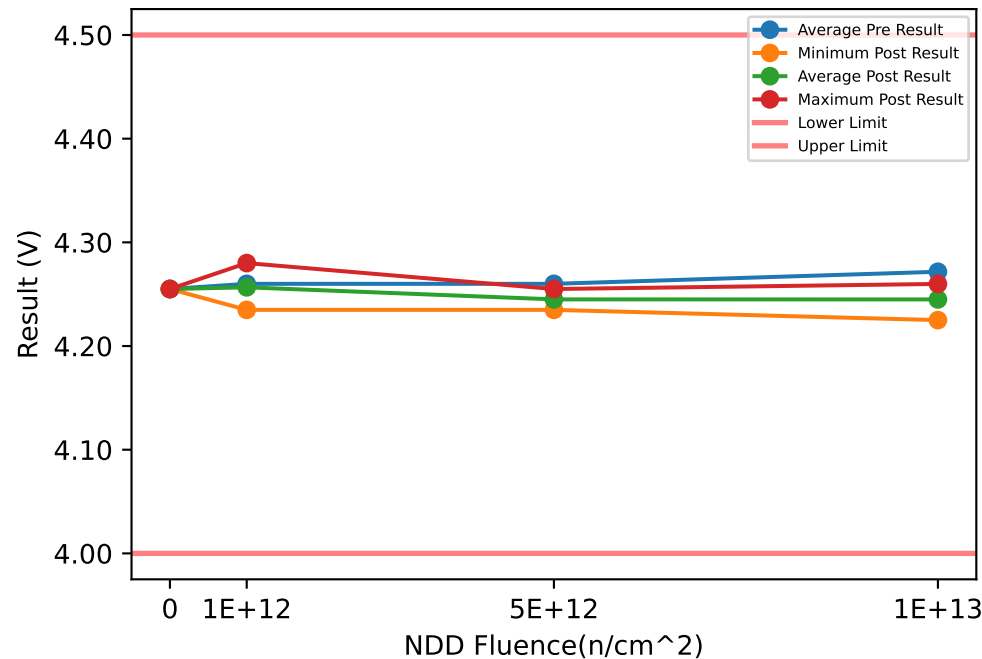


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.6725	6.6725	6.6725		6.6675	6.6675	6.6675		-0.005	-0.005	-0.005	
1e+12	6.6326	6.6576	6.7025	0.038994	6.6275	6.6525	6.6975	0.039026	-0.0051	-0.0050333	-0.005	5.7735e-05
5e+12	6.6275	6.6442	6.6675	0.020801	6.6026	6.6209	6.6475	0.02359	-0.0251	-0.023333	-0.02	0.0028885
1e+13	6.5924	6.6475	6.6926	0.050843	6.5476	6.6025	6.6425	0.049188	-0.0501	-0.044967	-0.04	0.0050521

Device Test: 80.1 V_BP5L_TH_RISE(UVLO BP5L Rise Thresh VIN_10V)

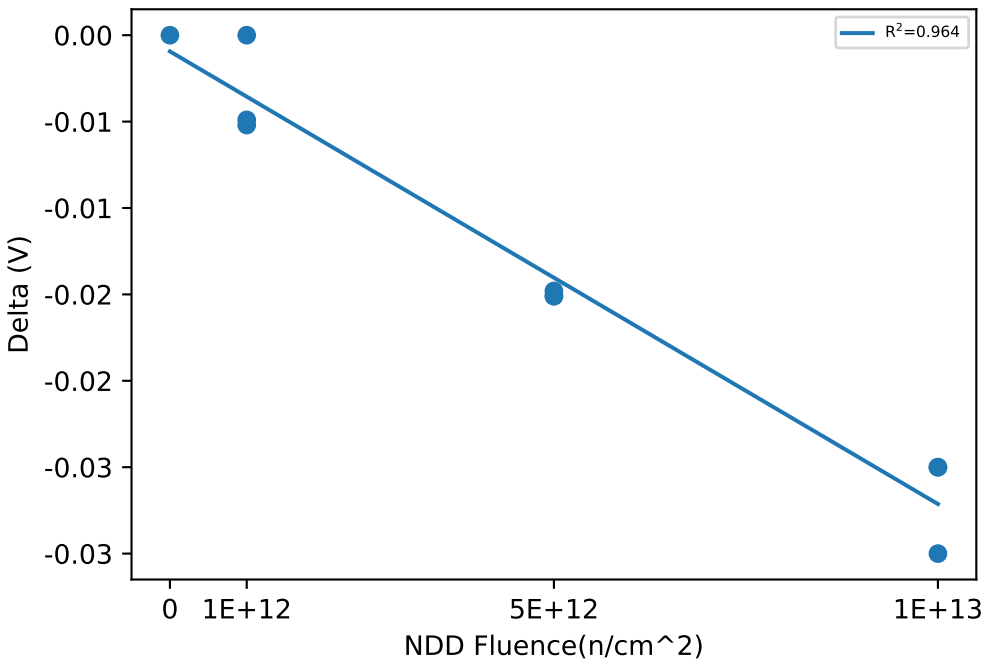
NDD vs Result Stats



Test Results (Lower Limit = 4.0, Upper Limit = 4.5 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.28	4.28	0
551	1e+12	NDD	4.2401	4.2349	-0.0052
552	1e+12	NDD	4.2599	4.255	-0.0049
553	5e+12	NDD	4.2599	4.2451	-0.0148
554	5e+12	NDD	4.25	4.2349	-0.0151
555	5e+12	NDD	4.2701	4.255	-0.0151
556	1e+13	NDD	4.25	4.225	-0.025
557	1e+13	NDD	4.28	4.25	-0.03
558	1e+13	NDD	4.2849	4.2599	-0.025
559	0	NDD, Ctrl	4.255	4.255	0

NDD vs Post - Pre Exposure Delta

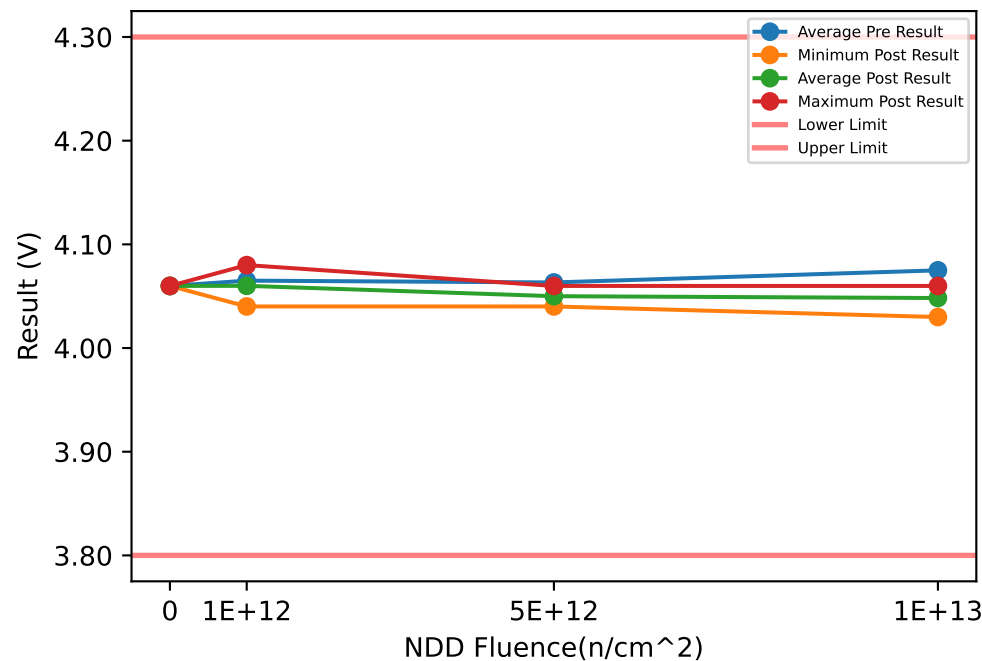


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.255	4.255	4.255		4.255	4.255	4.255		0	0	0	
1e+12	4.2401	4.26	4.28	0.01995	4.2349	4.2566	4.28	0.022594	-0.0052	-0.0033667	0	0.0029195
5e+12	4.25	4.26	4.2701	0.01005	4.2349	4.245	4.255	0.01005	-0.0151	-0.015	-0.0148	0.00017321
1e+13	4.25	4.2716	4.2849	0.018895	4.225	4.245	4.2599	0.017986	-0.03	-0.026667	-0.025	0.0028868

Device Test: 80.2 V_BP5L_TH_FALL(UVLO BP5L Fall Thresh VIN_10V)

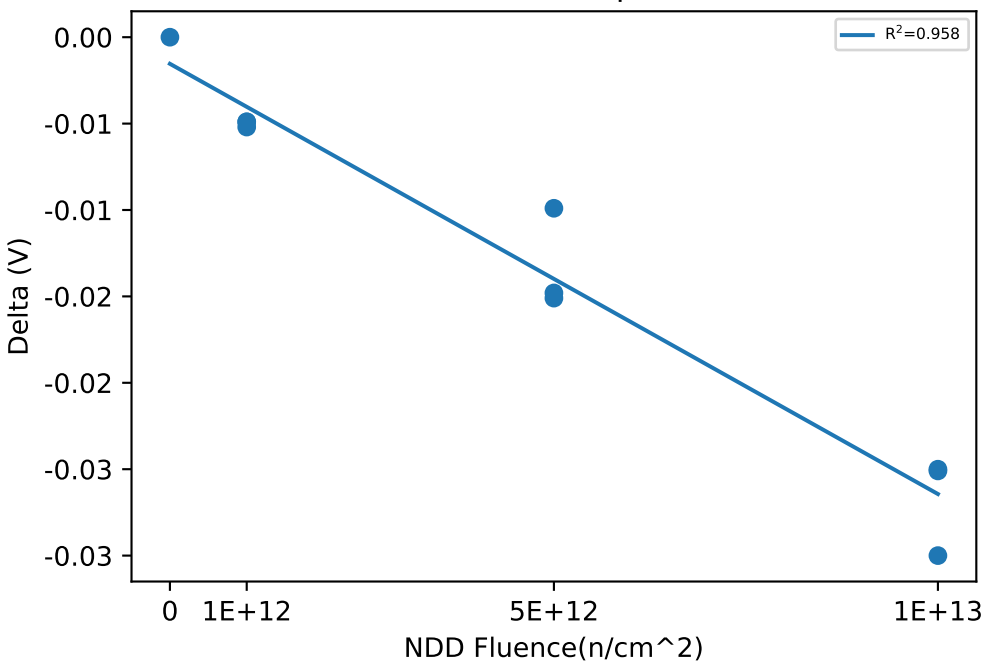
NDD vs Result Stats



Test Results (Lower Limit = 3.8, Upper Limit = 4.3 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.0849	4.08	-0.0049
551	1e+12	NDD	4.045	4.0401	-0.0049
552	1e+12	NDD	4.0651	4.0599	-0.0052
553	5e+12	NDD	4.0599	4.05	-0.0099
554	5e+12	NDD	4.0549	4.0401	-0.0148
555	5e+12	NDD	4.075	4.0599	-0.0151
556	1e+13	NDD	4.0549	4.0299	-0.025
557	1e+13	NDD	4.08	4.0549	-0.0251
558	1e+13	NDD	4.0899	4.0599	-0.03
559	0	NDD, Ctrl	4.0599	4.0599	0

NDD vs Post - Pre Exposure Delta

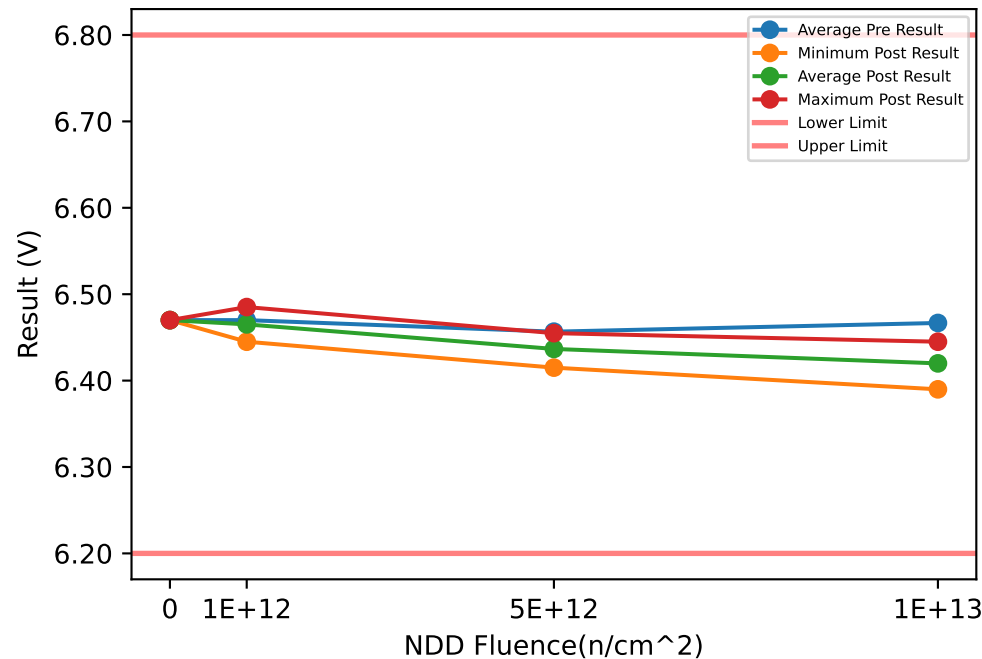


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.0599	4.0599	4.0599		4.0599	4.0599	4.0599		0	0	0	
1e+12	4.045	4.065	4.0849	0.01995	4.0401	4.06	4.08	0.01995	-0.0052	-0.005	-0.0049	0.00017321
5e+12	4.0549	4.0633	4.075	0.010464	4.0401	4.05	4.0599	0.0099	-0.0151	-0.013267	-0.0099	0.0029195
1e+13	4.0549	4.0749	4.0899	0.018042	4.0299	4.0482	4.0599	0.016073	-0.03	-0.0267	-0.025	0.0028583

Device Test: 80.4 V_BP7L_TH_RISE(UVLO BP7L Rise Thresh VIN_10V)

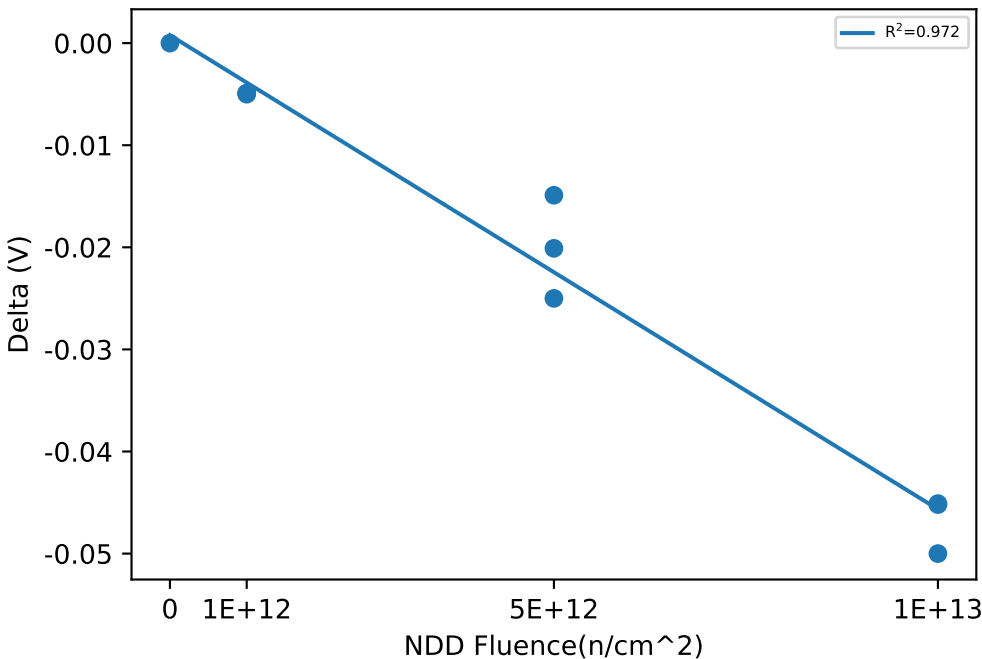
NDD vs Result Stats



Test Results (Lower Limit = 6.2, Upper Limit = 6.8 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	6.47	6.4651	-0.0049
551	1e+12	NDD	6.4499	6.445	-0.0049
552	1e+12	NDD	6.4901	6.4851	-0.005
553	5e+12	NDD	6.4799	6.4549	-0.025
554	5e+12	NDD	6.4351	6.415	-0.0201
555	5e+12	NDD	6.4549	6.44	-0.0149
556	1e+13	NDD	6.4351	6.3899	-0.0452
557	1e+13	NDD	6.47	6.4249	-0.0451
558	1e+13	NDD	6.495	6.445	-0.05
559	0	NDD, Ctrl	6.47	6.47	0

NDD vs Post - Pre Exposure Delta

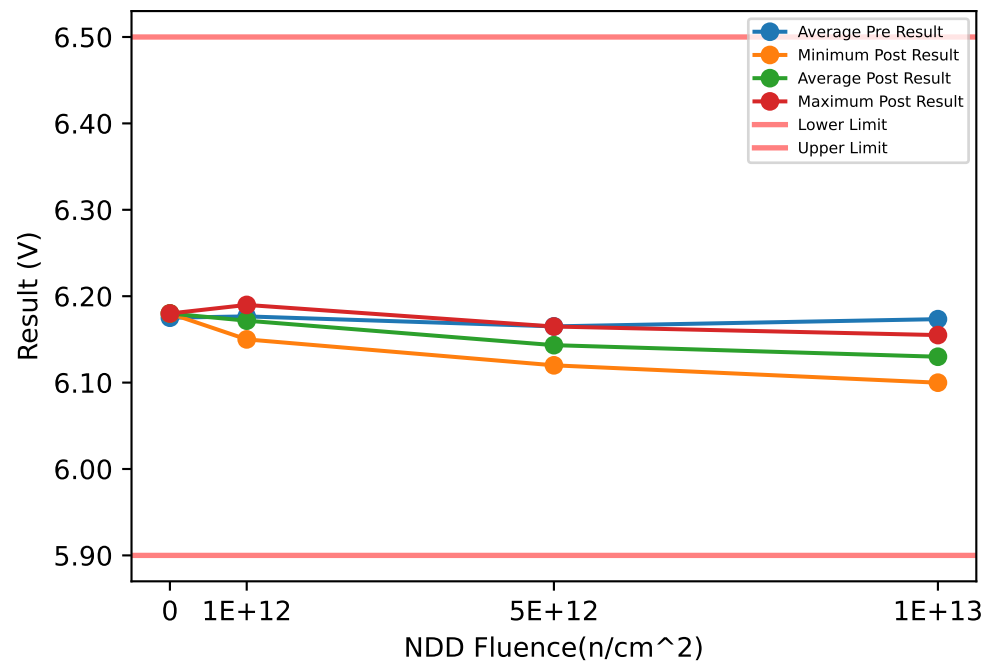


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.47	6.47	6.47		6.47	6.47	6.47		0	0	0	
1e+12	6.4499	6.47	6.4901	0.0201	6.445	6.4651	6.4851	0.02005	-0.005	-0.0049333	-0.0049	5.7735e-05
5e+12	6.4351	6.4566	6.4799	0.02245	6.415	6.4366	6.4549	0.020162	-0.025	-0.02	-0.0149	0.0050507
1e+13	6.4351	6.4667	6.495	0.030086	6.3899	6.4199	6.445	0.027884	-0.05	-0.046767	-0.0451	0.0028006

Device Test: 80.5 V_BP7L_TH_FALL(UVLO BP7L Fall Thresh VIN_10V)

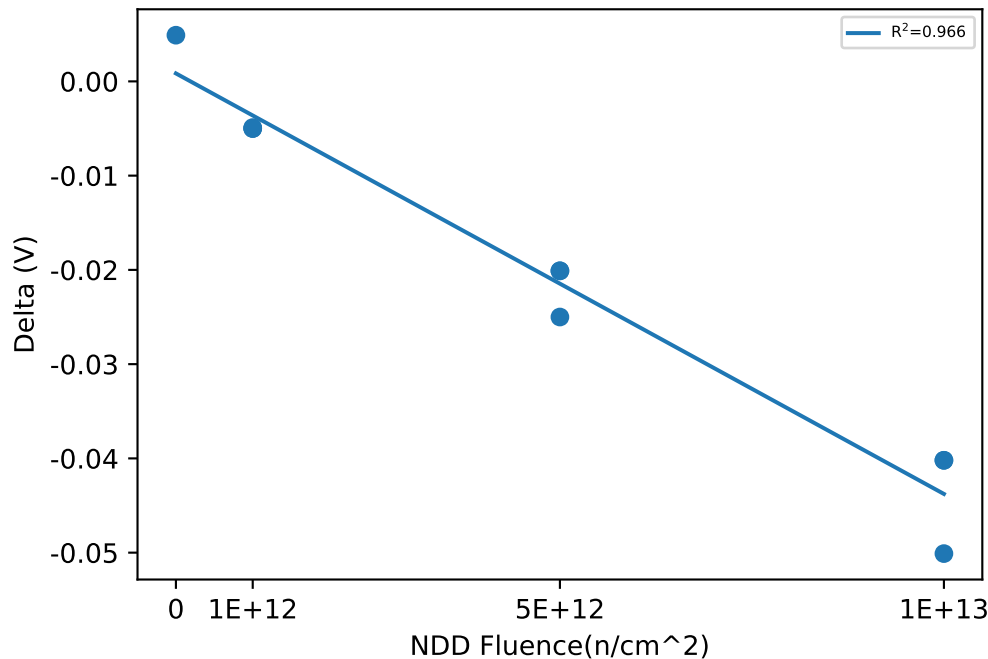
NDD vs Result Stats



Test Results (Lower Limit = 5.9, Upper Limit = 6.5 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	6.18	6.1751	-0.0049
551	1e+12	NDD	6.155	6.15	-0.005
552	1e+12	NDD	6.1949	6.1899	-0.005
553	5e+12	NDD	6.185	6.1649	-0.0201
554	5e+12	NDD	6.1401	6.12	-0.0201
555	5e+12	NDD	6.1701	6.1451	-0.025
556	1e+13	NDD	6.1401	6.0999	-0.0402
557	1e+13	NDD	6.1751	6.1349	-0.0402
558	1e+13	NDD	6.2051	6.155	-0.0501
559	0	NDD, Ctrl	6.1751	6.18	0.0049

NDD vs Post - Pre Exposure Delta

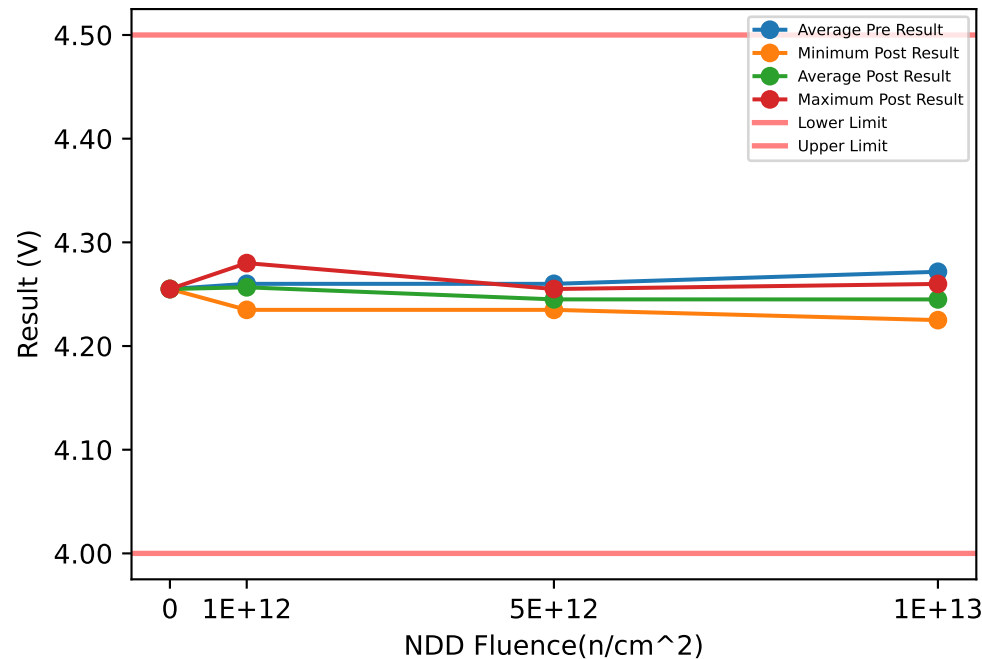


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.1751	6.1751	6.1751		6.18	6.18	6.18		0.0049	0.0049	0.0049	
1e+12	6.155	6.1766	6.1949	0.020162	6.15	6.1717	6.1899	0.02017	-0.005	-0.0049667	-0.0049	5.7735e-05
5e+12	6.1401	6.1651	6.185	0.022869	6.12	6.1433	6.1649	0.022502	-0.025	-0.021733	-0.0201	0.002829
1e+13	6.1401	6.1734	6.2051	0.032532	6.0999	6.1299	6.155	0.027884	-0.0501	-0.0435	-0.0402	0.0057158

Device Test: 81.1 V_BP5L_TH_RISE(UVLO BP5L Rise Thresh VIN_12V)

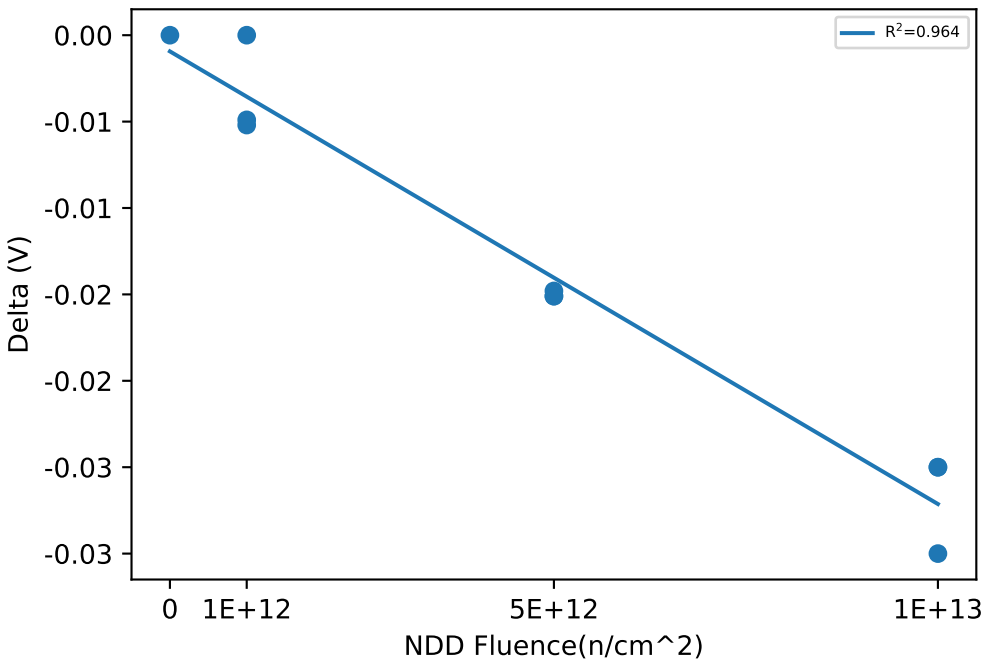
NDD vs Result Stats



Test Results (Lower Limit = 4.0, Upper Limit = 4.5 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.28	4.28	0
551	1e+12	NDD	4.2401	4.2349	-0.0052
552	1e+12	NDD	4.2599	4.255	-0.0049
553	5e+12	NDD	4.2599	4.2451	-0.0148
554	5e+12	NDD	4.25	4.2349	-0.0151
555	5e+12	NDD	4.2701	4.255	-0.0151
556	1e+13	NDD	4.25	4.225	-0.025
557	1e+13	NDD	4.28	4.25	-0.03
558	1e+13	NDD	4.2849	4.2599	-0.025
559	0	NDD, Ctrl	4.255	4.255	0

NDD vs Post - Pre Exposure Delta

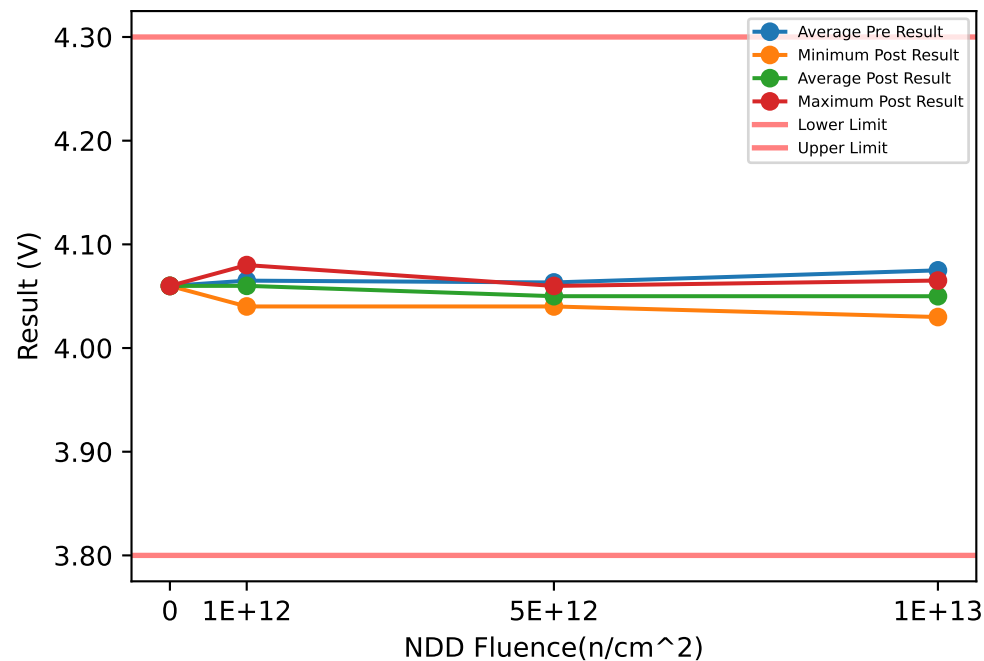


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.255	4.255	4.255		4.255	4.255	4.255		0	0	0	
1e+12	4.2401	4.26	4.28	0.01995	4.2349	4.2566	4.28	0.022594	-0.0052	-0.0033667	0	0.0029195
5e+12	4.25	4.26	4.2701	0.01005	4.2349	4.245	4.255	0.01005	-0.0151	-0.015	-0.0148	0.00017321
1e+13	4.25	4.2716	4.2849	0.018895	4.225	4.245	4.2599	0.017986	-0.03	-0.026667	-0.025	0.0028868

Device Test: 81.2 V_BP5L_TH_FALL(UVLO BP5L Fall Thresh VIN_12V)

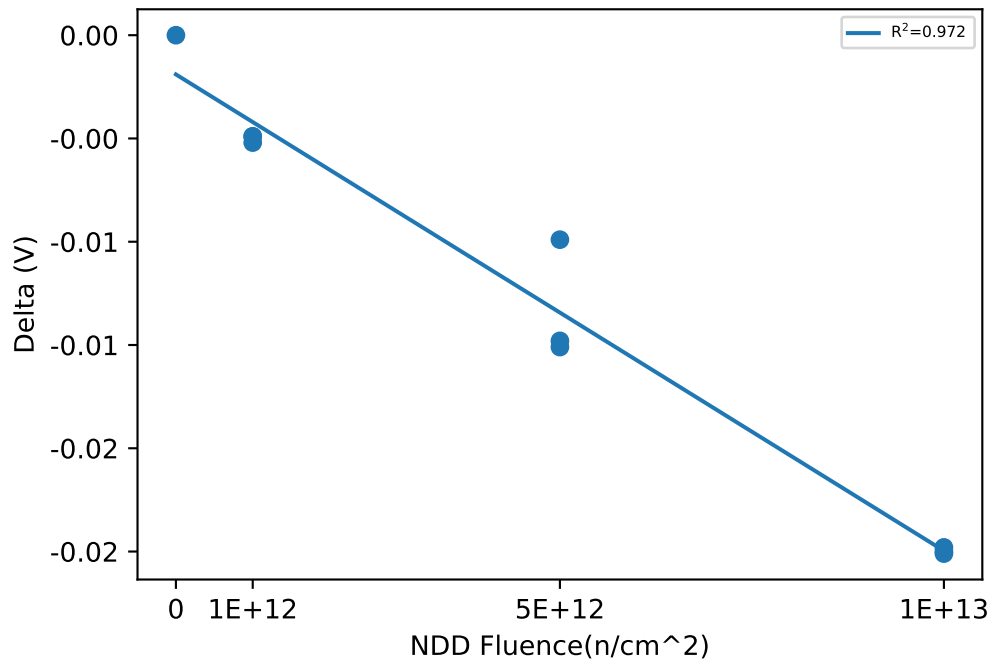
NDD vs Result Stats



Test Results (Lower Limit = 3.8, Upper Limit = 4.3 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.0849	4.08	-0.0049
551	1e+12	NDD	4.045	4.0401	-0.0049
552	1e+12	NDD	4.0651	4.0599	-0.0052
553	5e+12	NDD	4.0599	4.05	-0.0099
554	5e+12	NDD	4.0549	4.0401	-0.0148
555	5e+12	NDD	4.075	4.0599	-0.0151
556	1e+13	NDD	4.0549	4.0299	-0.025
557	1e+13	NDD	4.08	4.0549	-0.0251
558	1e+13	NDD	4.0899	4.0651	-0.0248
559	0	NDD, Ctrl	4.0599	4.0599	0

NDD vs Post - Pre Exposure Delta

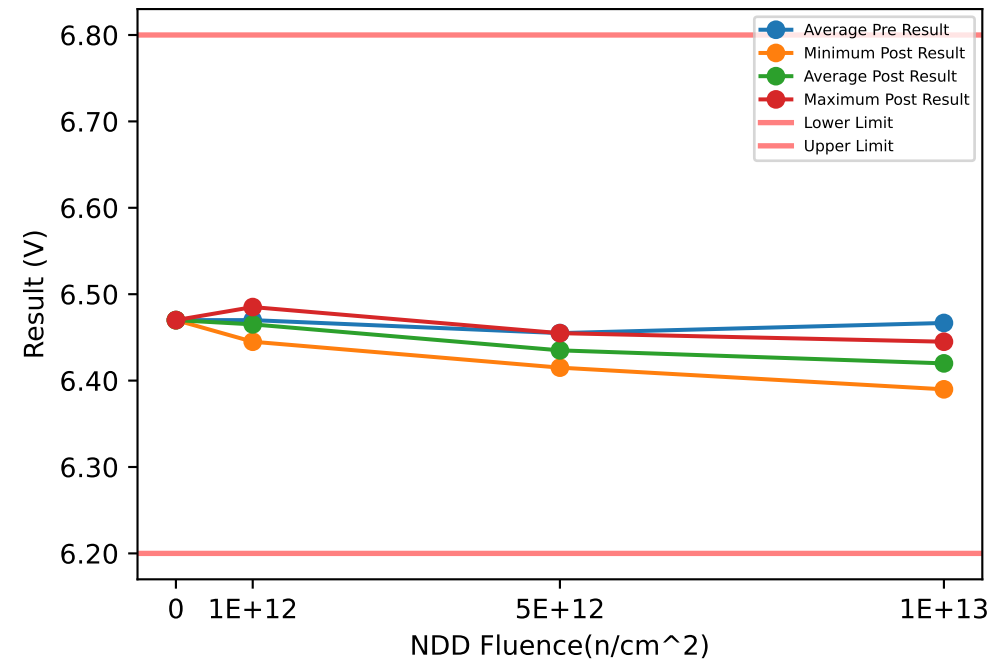


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.0599	4.0599	4.0599		4.0599	4.0599	4.0599		0	0	0	
1e+12	4.045	4.065	4.0849	0.01995	4.0401	4.06	4.08	0.01995	-0.0052	-0.005	-0.0049	0.00017321
5e+12	4.0549	4.0633	4.075	0.010464	4.0401	4.05	4.0599	0.0099	-0.0151	-0.013267	-0.0099	0.0029195
1e+13	4.0549	4.0749	4.0899	0.018042	4.0299	4.05	4.0651	0.018111	-0.0251	-0.024967	-0.0248	0.00015275

Device Test: 81.4 V_BP7L_TH_RISE(UVLO BP7L Rise Thresh VIN_12V)

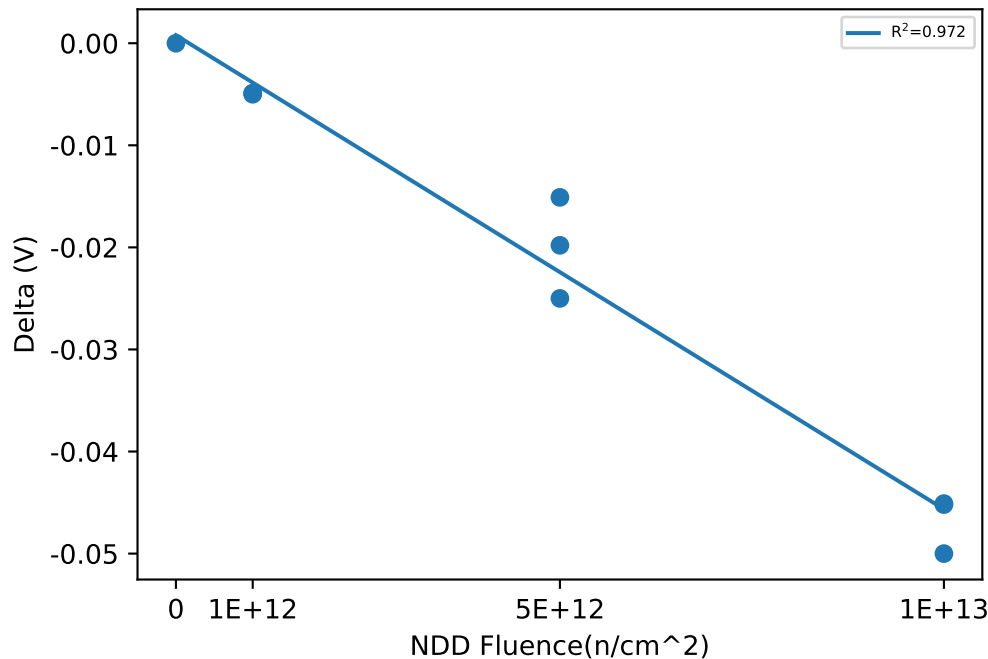
NDD vs Result Stats



Test Results (Lower Limit = 6.2, Upper Limit = 6.8 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	6.47	6.4651	-0.0049
551	1e+12	NDD	6.4499	6.445	-0.0049
552	1e+12	NDD	6.4901	6.4851	-0.005
553	5e+12	NDD	6.4799	6.4549	-0.025
554	5e+12	NDD	6.4301	6.415	-0.0151
555	5e+12	NDD	6.4549	6.4351	-0.0198
556	1e+13	NDD	6.4351	6.3899	-0.0452
557	1e+13	NDD	6.47	6.4249	-0.0451
558	1e+13	NDD	6.495	6.445	-0.05
559	0	NDD, Ctrl	6.47	6.47	0

NDD vs Post - Pre Exposure Delta

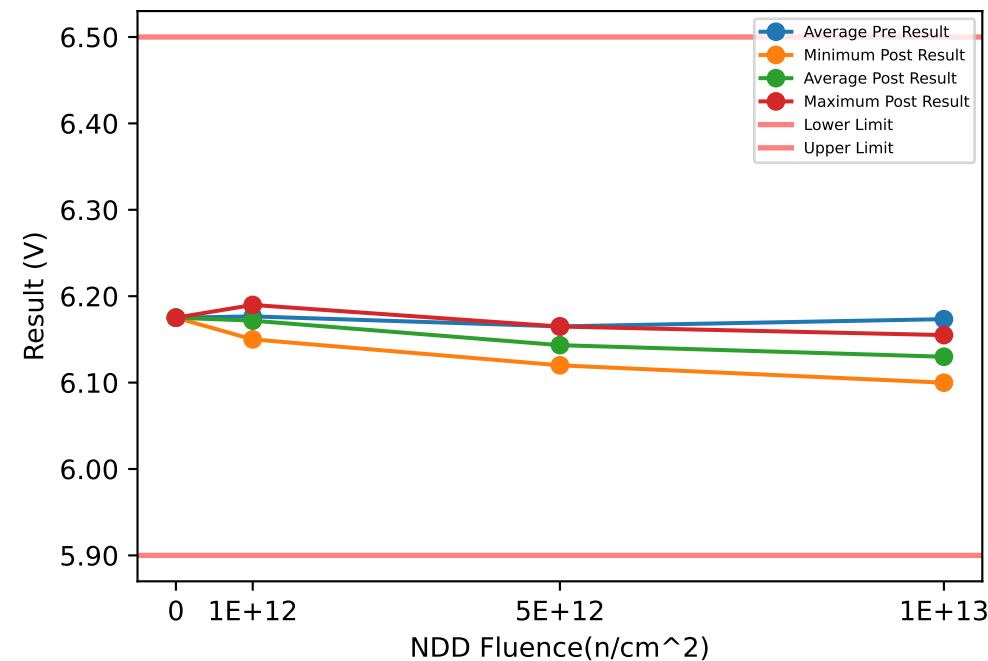


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.47	6.47	6.47		6.47	6.47	6.47		0	0	0	
1e+12	6.4499	6.47	6.4901	0.0201	6.445	6.4651	6.4851	0.02005	-0.005	-0.0049333	-0.0049	5.7735e-05
5e+12	6.4301	6.455	6.4799	0.0249	6.415	6.435	6.4549	0.01995	-0.025	-0.019967	-0.0151	0.0049521
1e+13	6.4351	6.4667	6.495	0.030086	6.3899	6.4199	6.445	0.027884	-0.05	-0.046767	-0.0451	0.0028006

Device Test: 81.5 V_BP7L_TH_FALL(UVLO BP7L Fall Thresh VIN_12V)

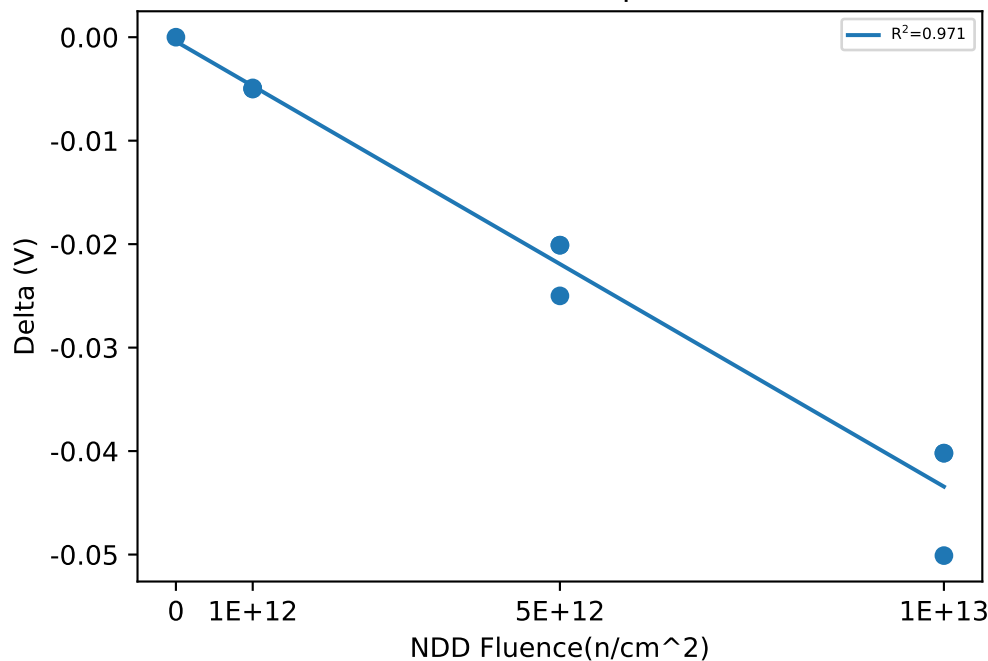
NDD vs Result Stats



Test Results (Lower Limit = 5.9, Upper Limit = 6.5 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	6.18	6.1751	-0.0049
551	1e+12	NDD	6.155	6.15	-0.005
552	1e+12	NDD	6.1949	6.1899	-0.005
553	5e+12	NDD	6.185	6.1649	-0.0201
554	5e+12	NDD	6.1401	6.12	-0.0201
555	5e+12	NDD	6.1701	6.1451	-0.025
556	1e+13	NDD	6.1401	6.0999	-0.0402
557	1e+13	NDD	6.1751	6.1349	-0.0402
558	1e+13	NDD	6.2051	6.155	-0.0501
559	0	NDD, Ctrl	6.1751	6.1751	0

NDD vs Post - Pre Exposure Delta

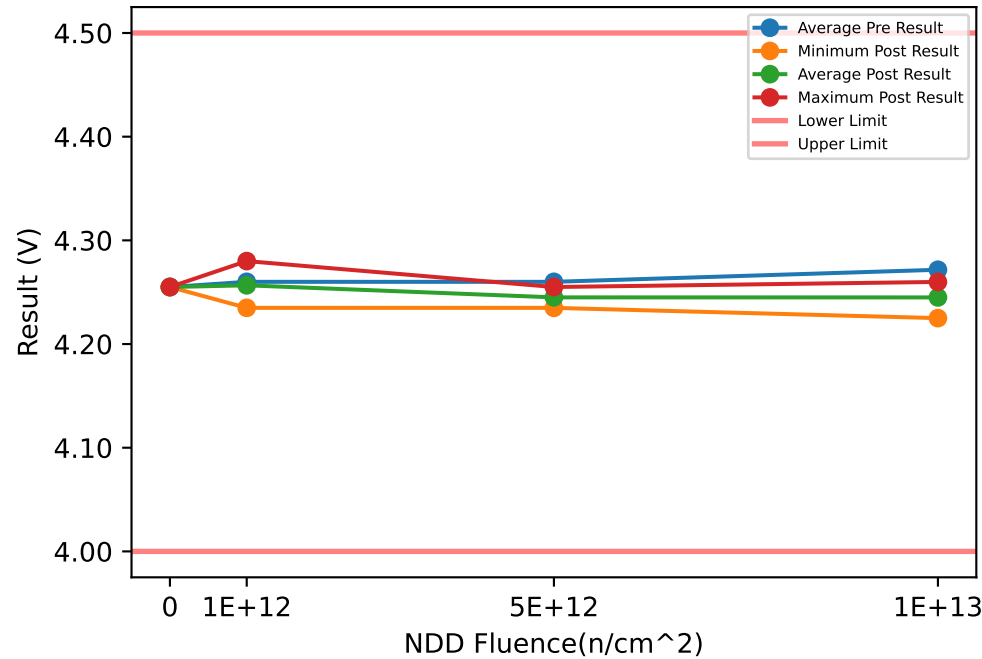


Test Statistics (V)

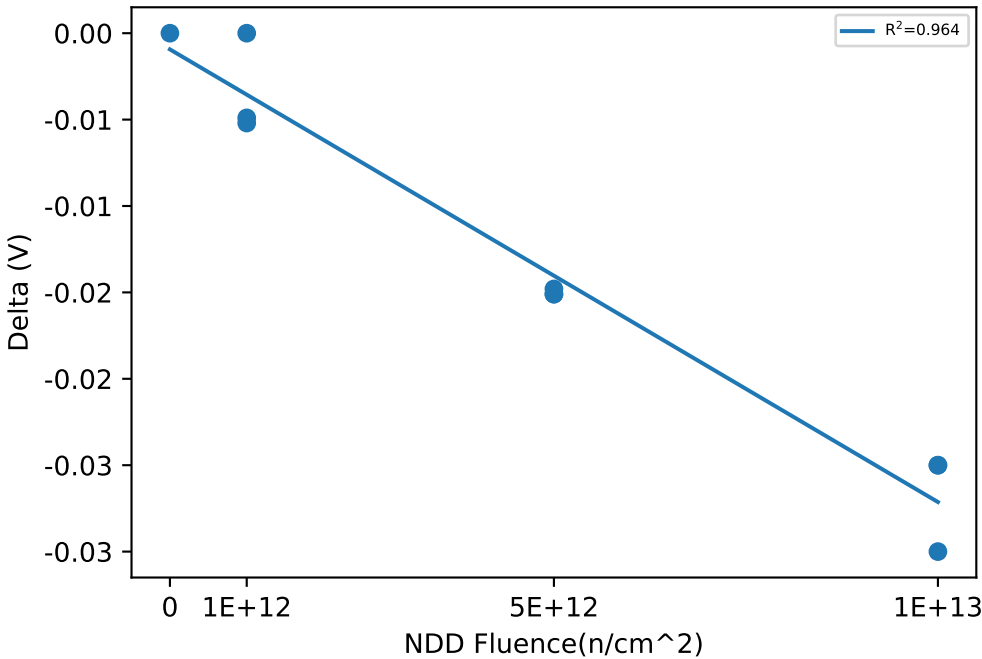
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.1751	6.1751	6.1751		6.1751	6.1751	6.1751		0	0	0	
1e+12	6.155	6.1766	6.1949	0.020162	6.15	6.1717	6.1899	0.02017	-0.005	-0.0049667	-0.0049	5.7735e-05
5e+12	6.1401	6.1651	6.185	0.022869	6.12	6.1433	6.1649	0.022502	-0.025	-0.021733	-0.0201	0.002829
1e+13	6.1401	6.1734	6.2051	0.032532	6.0999	6.1299	6.155	0.027884	-0.0501	-0.0435	-0.0402	0.0057158

Device Test: 82.1 V_BP5L_TH_RISE(UVLO BP5L Rise Thresh VIN_14V)

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 4.0, Upper Limit = 4.5 (V))

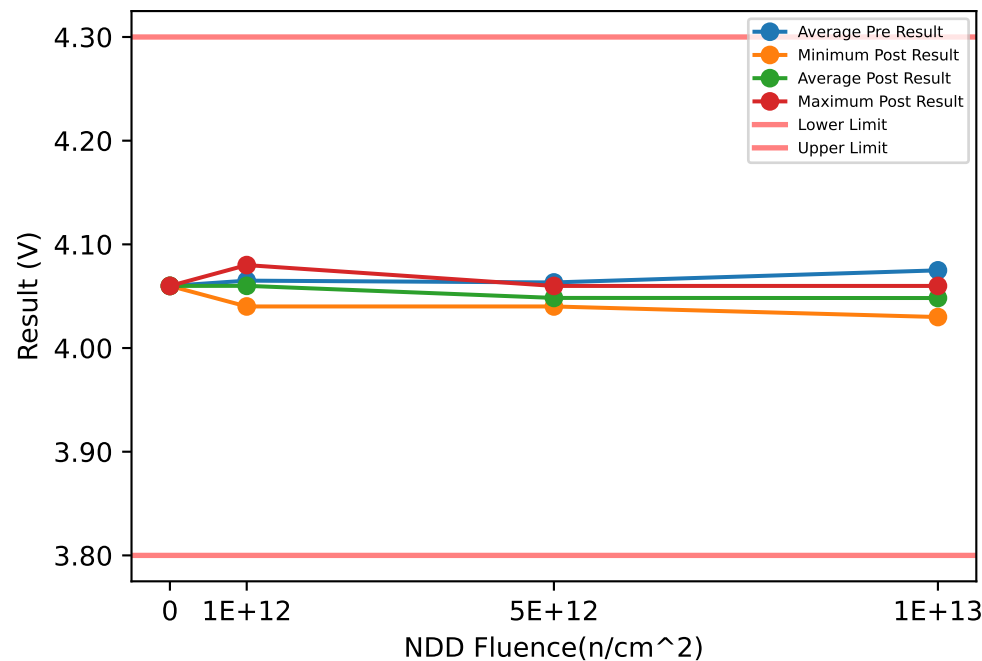
Serial #	Fluence(n/cm ²)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.28	4.28	0
551	1e+12	NDD	4.2401	4.2349	-0.0052
552	1e+12	NDD	4.2599	4.255	-0.0049
553	5e+12	NDD	4.2599	4.2451	-0.0148
554	5e+12	NDD	4.25	4.2349	-0.0151
555	5e+12	NDD	4.2701	4.255	-0.0151
556	1e+13	NDD	4.25	4.225	-0.025
557	1e+13	NDD	4.28	4.25	-0.03
558	1e+13	NDD	4.2849	4.2599	-0.025
559	0	NDD, Ctrl	4.255	4.255	0

Test Statistics (V)

Fluence(n/cm ²)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.255	4.255	4.255		4.255	4.255	4.255		0	0	0	
1e+12	4.2401	4.26	4.28	0.01995	4.2349	4.2566	4.28	0.022594	-0.0052	-0.0033667	0	0.0029195
5e+12	4.25	4.26	4.2701	0.01005	4.2349	4.245	4.255	0.01005	-0.0151	-0.015	-0.0148	0.00017321
1e+13	4.25	4.2716	4.2849	0.018895	4.225	4.245	4.2599	0.017986	-0.03	-0.026667	-0.025	0.0028868

Device Test: 82.2 V_BP5L_TH_FALL(UVLO BP5L Fall Thresh VIN_14V)

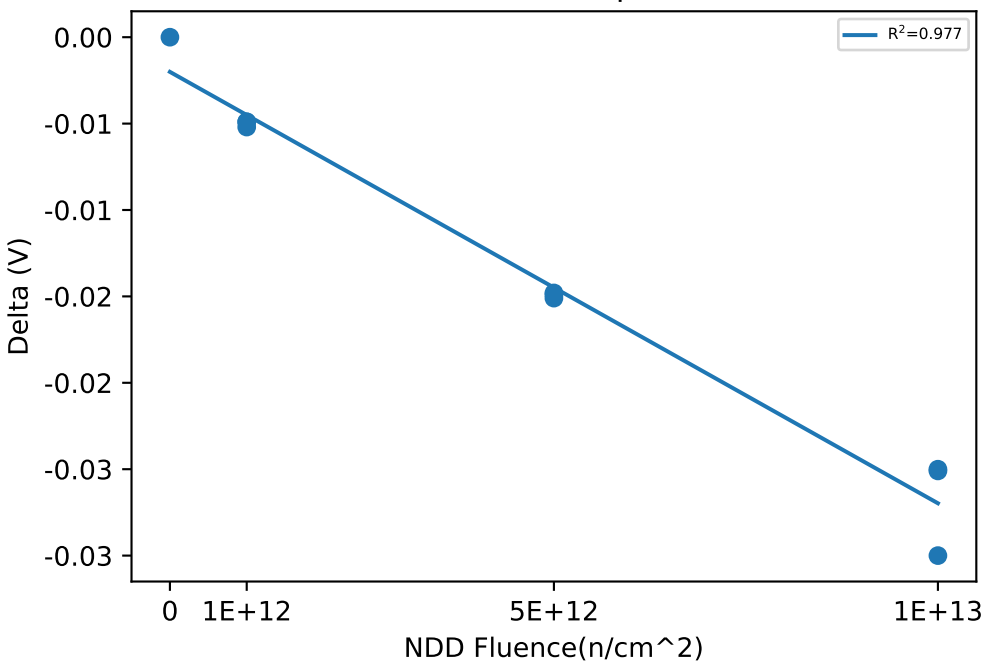
NDD vs Result Stats



Test Results (Lower Limit = 3.8, Upper Limit = 4.3 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.0849	4.08	-0.0049
551	1e+12	NDD	4.045	4.0401	-0.0049
552	1e+12	NDD	4.0651	4.0599	-0.0052
553	5e+12	NDD	4.0599	4.045	-0.0149
554	5e+12	NDD	4.0549	4.0401	-0.0148
555	5e+12	NDD	4.075	4.0599	-0.0151
556	1e+13	NDD	4.0549	4.0299	-0.025
557	1e+13	NDD	4.08	4.0549	-0.0251
558	1e+13	NDD	4.0899	4.0599	-0.03
559	0	NDD, Ctrl	4.0599	4.0599	0

NDD vs Post - Pre Exposure Delta

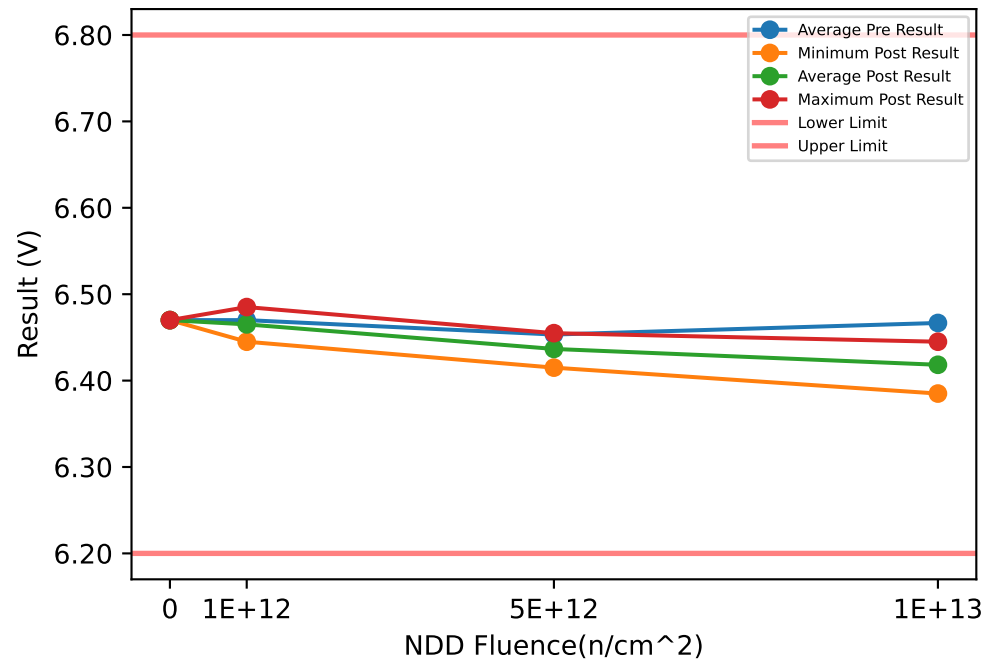


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.0599	4.0599	4.0599		4.0599	4.0599	4.0599		0	0	0	
1e+12	4.045	4.065	4.0849	0.01995	4.0401	4.06	4.08	0.01995	-0.0052	-0.005	-0.0049	0.00017321
5e+12	4.0549	4.0633	4.075	0.010464	4.0401	4.0483	4.0599	0.010312	-0.0151	-0.014933	-0.0148	0.00015275
1e+13	4.0549	4.0749	4.0899	0.018042	4.0299	4.0482	4.0599	0.016073	-0.03	-0.0267	-0.025	0.0028583

Device Test: 82.4 V_BP7L_TH_RISE(UVLO BP7L Rise Thresh VIN_14V)

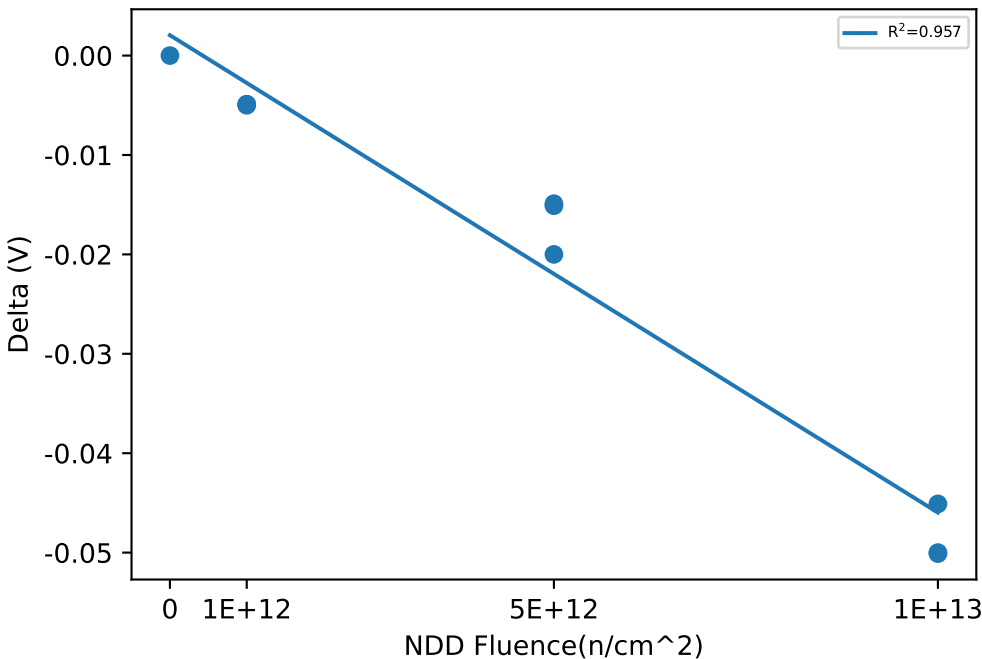
NDD vs Result Stats



Test Results (Lower Limit = 6.2, Upper Limit = 6.8 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	6.47	6.4651	-0.0049
551	1e+12	NDD	6.4499	6.445	-0.0049
552	1e+12	NDD	6.4901	6.4851	-0.005
553	5e+12	NDD	6.4749	6.4549	-0.02
554	5e+12	NDD	6.4301	6.415	-0.0151
555	5e+12	NDD	6.4549	6.44	-0.0149
556	1e+13	NDD	6.4351	6.385	-0.0501
557	1e+13	NDD	6.47	6.4249	-0.0451
558	1e+13	NDD	6.495	6.445	-0.05
559	0	NDD, Ctrl	6.47	6.47	0

NDD vs Post - Pre Exposure Delta

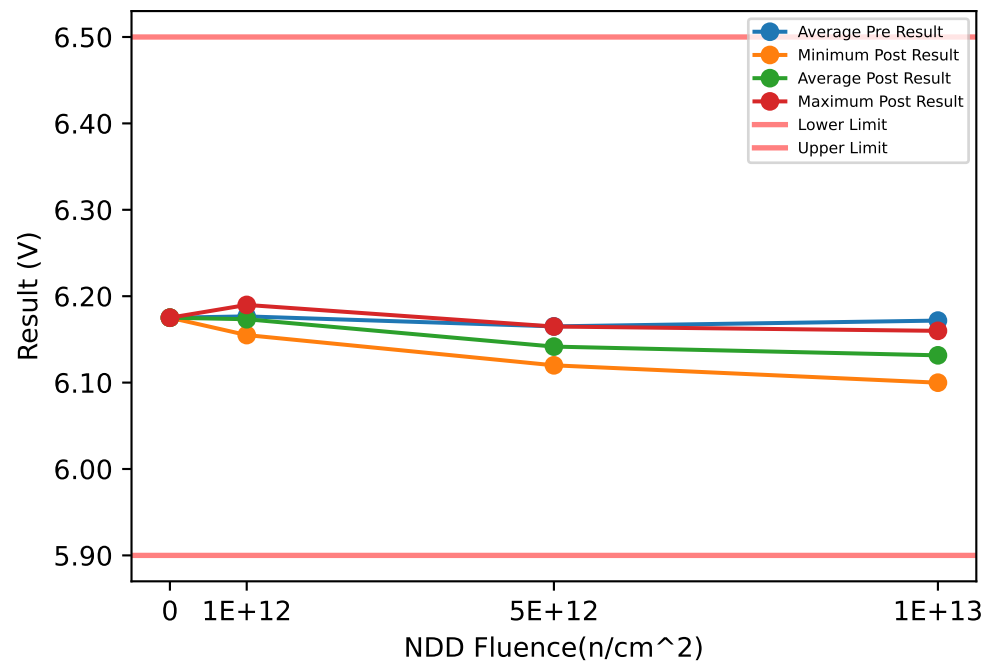


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.47	6.47	6.47		6.47	6.47	6.47		0	0	0	
1e+12	6.4499	6.47	6.4901	0.0201	6.445	6.4651	6.4851	0.02005	-0.005	-0.0049333	-0.0049	5.7735e-05
5e+12	6.4301	6.4533	6.4749	0.022443	6.415	6.4366	6.4549	0.020162	-0.02	-0.016667	-0.0149	0.0028885
1e+13	6.4351	6.4667	6.495	0.030086	6.385	6.4183	6.445	0.03054	-0.0501	-0.0484	-0.0451	0.0028583

Device Test: 82.5 V_BP7L_TH_FALL(UVLO BP7L Fall Thresh VIN_14V)

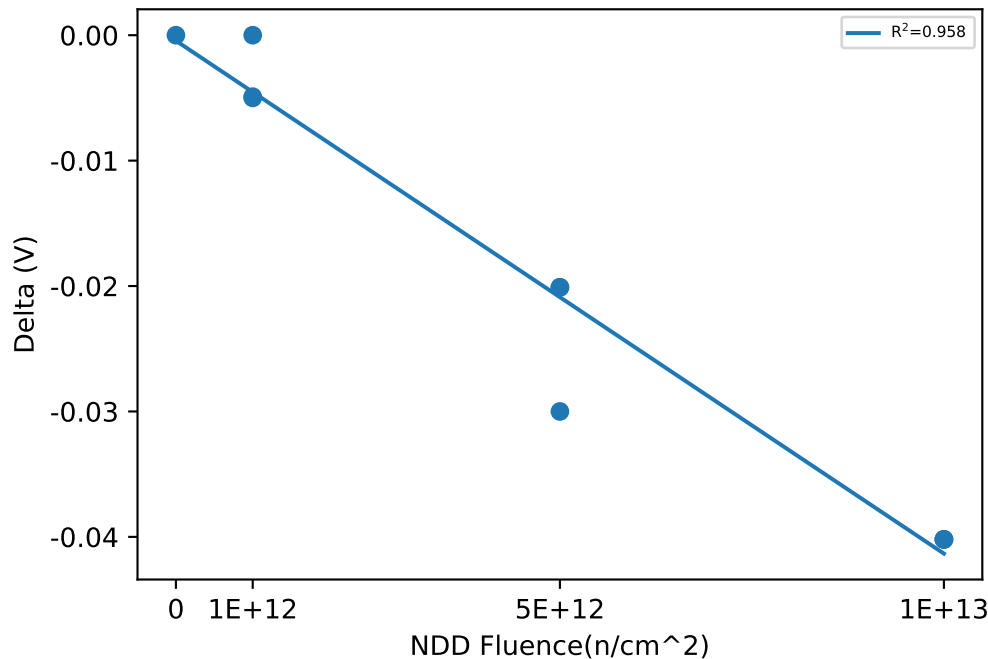
NDD vs Result Stats



Test Results (Lower Limit = 5.9, Upper Limit = 6.5 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	6.18	6.1751	-0.0049
551	1e+12	NDD	6.155	6.155	0
552	1e+12	NDD	6.1949	6.1899	-0.005
553	5e+12	NDD	6.185	6.1649	-0.0201
554	5e+12	NDD	6.1401	6.12	-0.0201
555	5e+12	NDD	6.1701	6.1401	-0.03
556	1e+13	NDD	6.1401	6.0999	-0.0402
557	1e+13	NDD	6.1751	6.1349	-0.0402
558	1e+13	NDD	6.2001	6.1599	-0.0402
559	0	NDD, Ctrl	6.1751	6.1751	0

NDD vs Post - Pre Exposure Delta

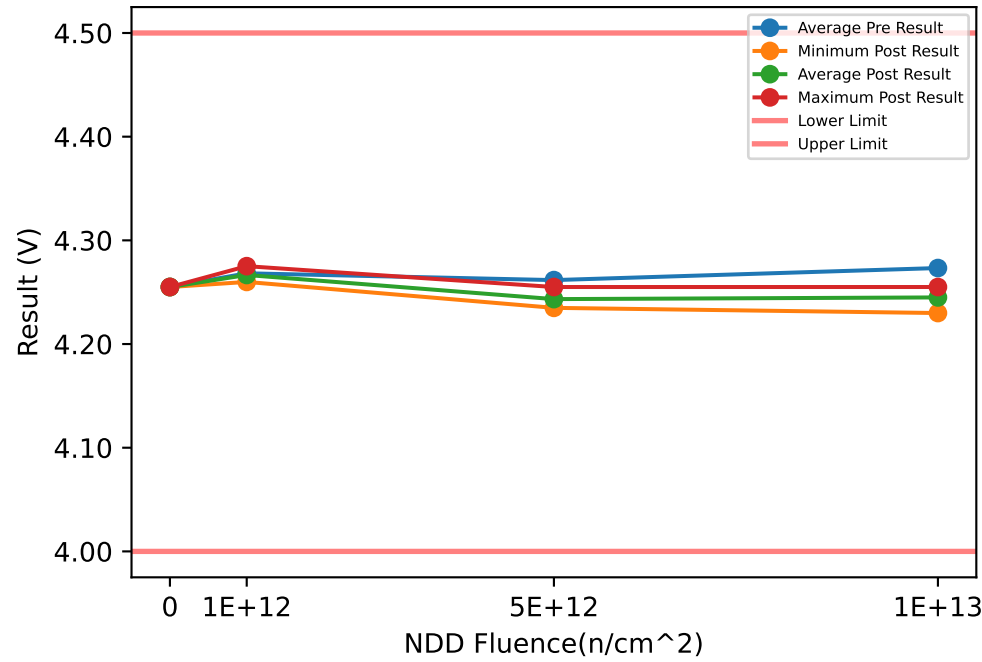


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.1751	6.1751	6.1751		6.1751	6.1751	6.1751		0	0	0	
1e+12	6.155	6.1766	6.1949	0.020162	6.155	6.1733	6.1899	0.017517	-0.005	-0.0033	0	0.0028583
5e+12	6.1401	6.1651	6.185	0.022869	6.12	6.1417	6.1649	0.022491	-0.03	-0.0234	-0.0201	0.0057158
1e+13	6.1401	6.1718	6.2001	0.030139	6.0999	6.1316	6.1599	0.030139	-0.0402	-0.0402	-0.0402	5.1329e-16

Device Test: 85.1 V_BP5H_TH_RISE(UVLO BP5H Rise Thresh VIN_10V)

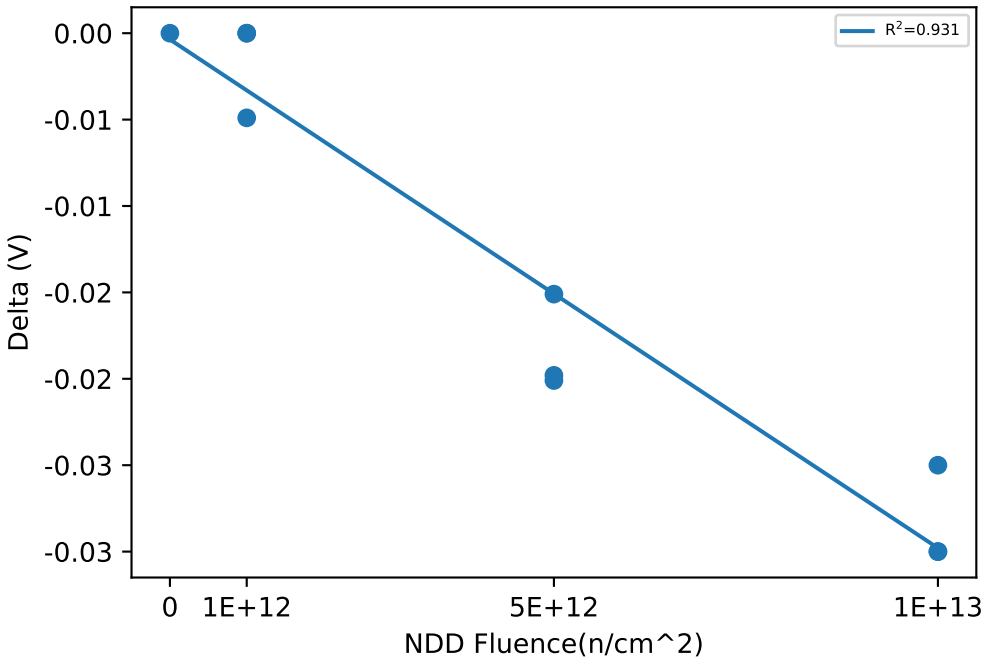
NDD vs Result Stats



Test Results (Lower Limit = 4.0, Upper Limit = 4.5 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.2648	4.2599	-0.0049
551	1e+12	NDD	4.2648	4.2648	0
552	1e+12	NDD	4.2751	4.2751	0
553	5e+12	NDD	4.255	4.2349	-0.0201
554	5e+12	NDD	4.2599	4.2401	-0.0198
555	5e+12	NDD	4.2701	4.255	-0.0151
556	1e+13	NDD	4.28	4.255	-0.025
557	1e+13	NDD	4.2599	4.2299	-0.03
558	1e+13	NDD	4.28	4.25	-0.03
559	0	NDD, Ctrl	4.255	4.255	0

NDD vs Post - Pre Exposure Delta

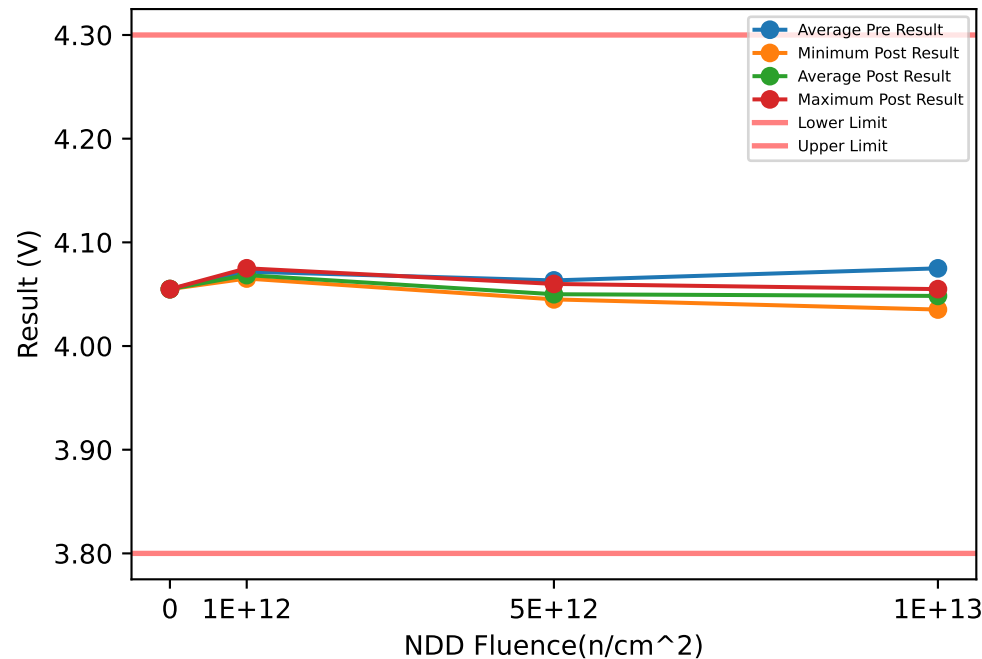


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.255	4.255	4.255		4.255	4.255	4.255		0	0	0	
1e+12	4.2648	4.2682	4.2751	0.0059467	4.2599	4.2666	4.2751	0.0077582	-0.0049	-0.0016333	0	0.002829
5e+12	4.255	4.2617	4.2701	0.0077035	4.2349	4.2433	4.255	0.010433	-0.0201	-0.018333	-0.0151	0.0028042
1e+13	4.2599	4.2733	4.28	0.011605	4.2299	4.245	4.255	0.013285	-0.03	-0.028333	-0.025	0.0028868

Device Test: 85.2 V_BP5H_TH_FALL(UVLO BP5H Fall Thresh VIN_10V)

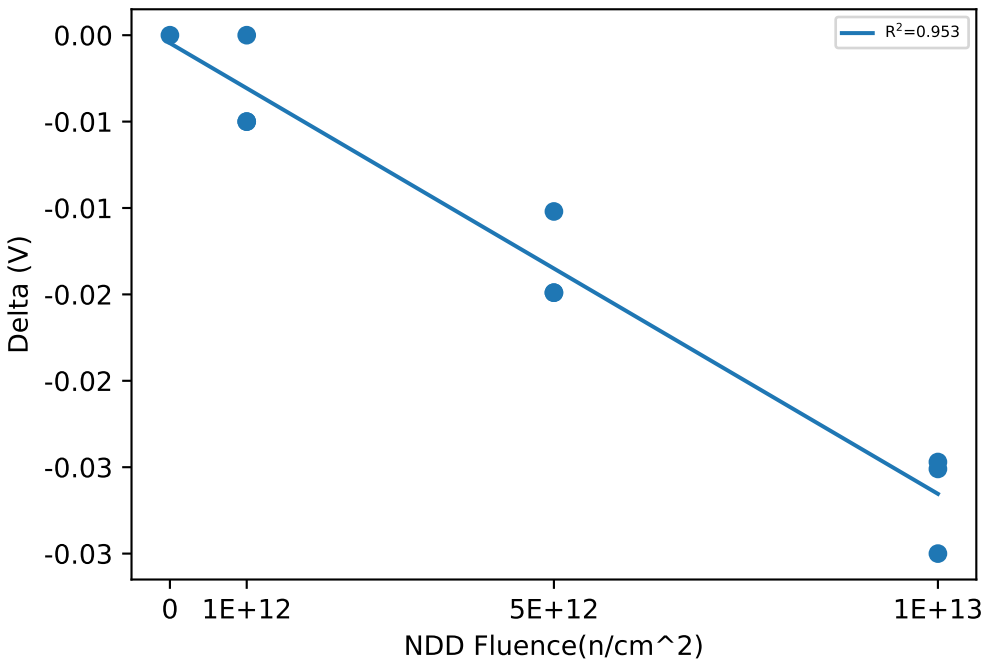
NDD vs Result Stats



Test Results (Lower Limit = 3.8, Upper Limit = 4.3 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.0651	4.0651	0
551	1e+12	NDD	4.0701	4.0651	-0.005
552	1e+12	NDD	4.08	4.075	-0.005
553	5e+12	NDD	4.0599	4.045	-0.0149
554	5e+12	NDD	4.0599	4.045	-0.0149
555	5e+12	NDD	4.0701	4.0599	-0.0102
556	1e+13	NDD	4.08	4.0549	-0.0251
557	1e+13	NDD	4.0599	4.0352	-0.0247
558	1e+13	NDD	4.0849	4.0549	-0.03
559	0	NDD, Ctrl	4.0549	4.0549	0

NDD vs Post - Pre Exposure Delta

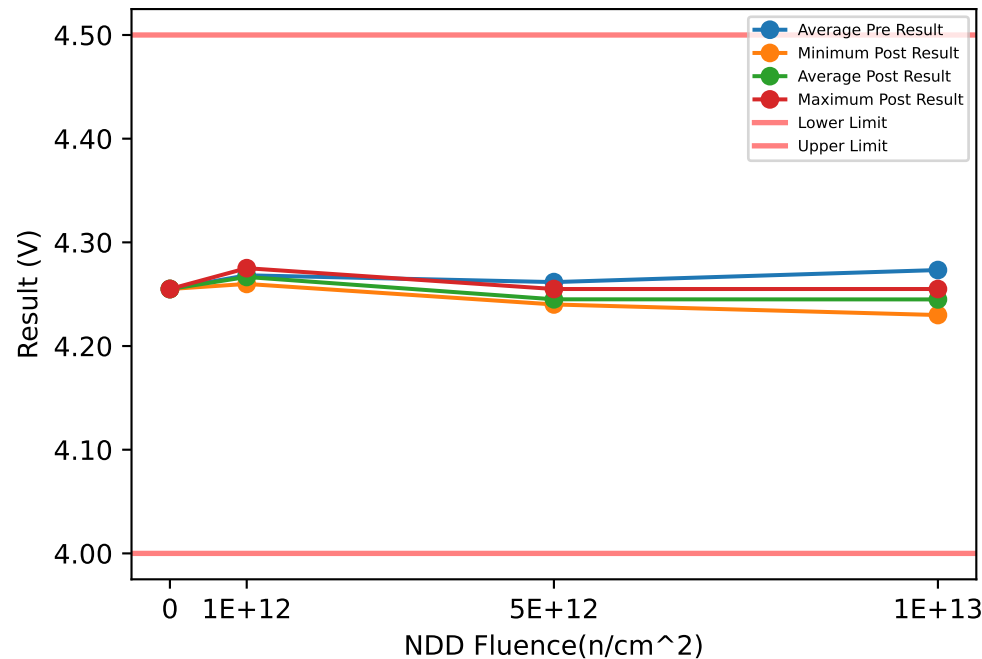


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.0549	4.0549	4.0549		4.0549	4.0549	4.0549		0	0	0	
1e+12	4.0651	4.0717	4.08	0.0075831	4.0651	4.0684	4.075	0.0057158	-0.005	-0.0033333	0	0.0028868
5e+12	4.0599	4.0633	4.0701	0.005889	4.045	4.05	4.0599	0.0086025	-0.0149	-0.013333	-0.0102	0.0027135
1e+13	4.0599	4.0749	4.0849	0.013248	4.0352	4.0483	4.0549	0.011374	-0.03	-0.0266	-0.0247	0.0029513

Device Test: 86.1 V_BP5H_TH_RISE(UVLO BP5H Rise Thresh VIN_12V)

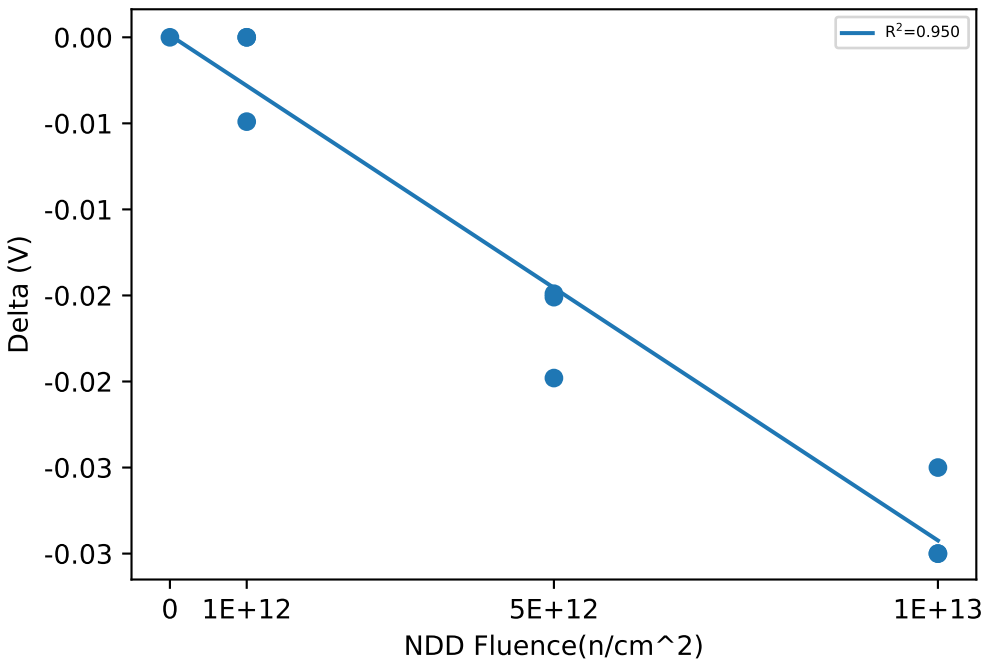
NDD vs Result Stats



Test Results (Lower Limit = 4.0, Upper Limit = 4.5 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.2648	4.2599	-0.0049
551	1e+12	NDD	4.2648	4.2648	0
552	1e+12	NDD	4.2751	4.2751	0
553	5e+12	NDD	4.255	4.2401	-0.0149
554	5e+12	NDD	4.2599	4.2401	-0.0198
555	5e+12	NDD	4.2701	4.255	-0.0151
556	1e+13	NDD	4.28	4.255	-0.025
557	1e+13	NDD	4.2599	4.2299	-0.03
558	1e+13	NDD	4.28	4.25	-0.03
559	0	NDD, Ctrl	4.255	4.255	0

NDD vs Post - Pre Exposure Delta

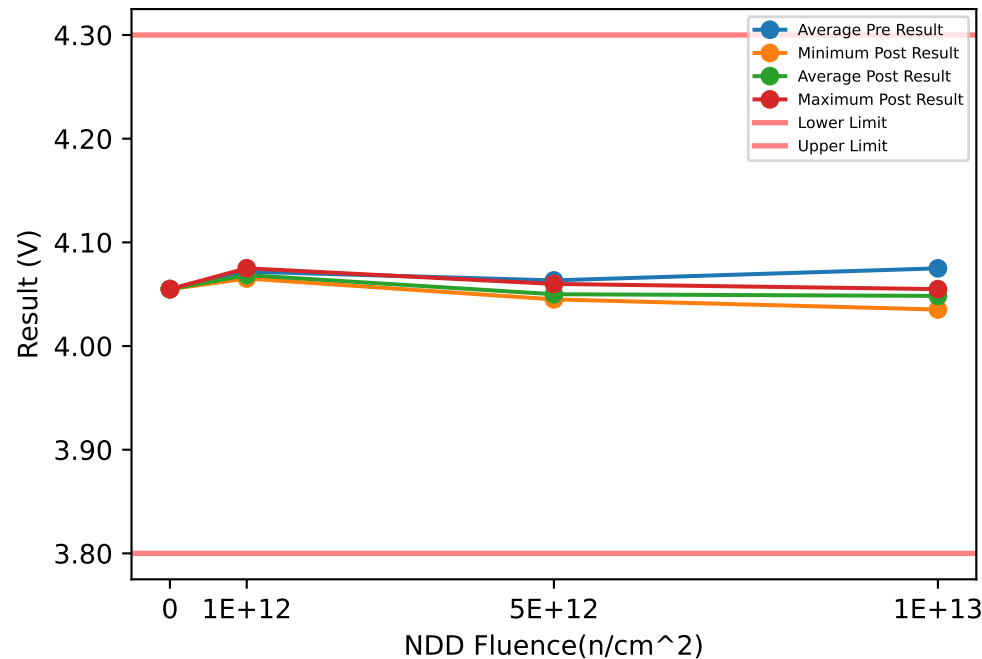


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.255	4.255	4.255		4.255	4.255	4.255		0	0	0	
1e+12	4.2648	4.2682	4.2751	0.0059467	4.2599	4.2666	4.2751	0.0077582	-0.0049	-0.0016333	0	0.002829
5e+12	4.255	4.2617	4.2701	0.0077035	4.2401	4.2451	4.255	0.0086025	-0.0198	-0.0166	-0.0149	0.0027731
1e+13	4.2599	4.2733	4.28	0.011605	4.2299	4.245	4.255	0.013285	-0.03	-0.028333	-0.025	0.0028868

Device Test: 86.2 V_BP5H_TH_FALL(UVLO BP5H Fall Thresh VIN_12V)

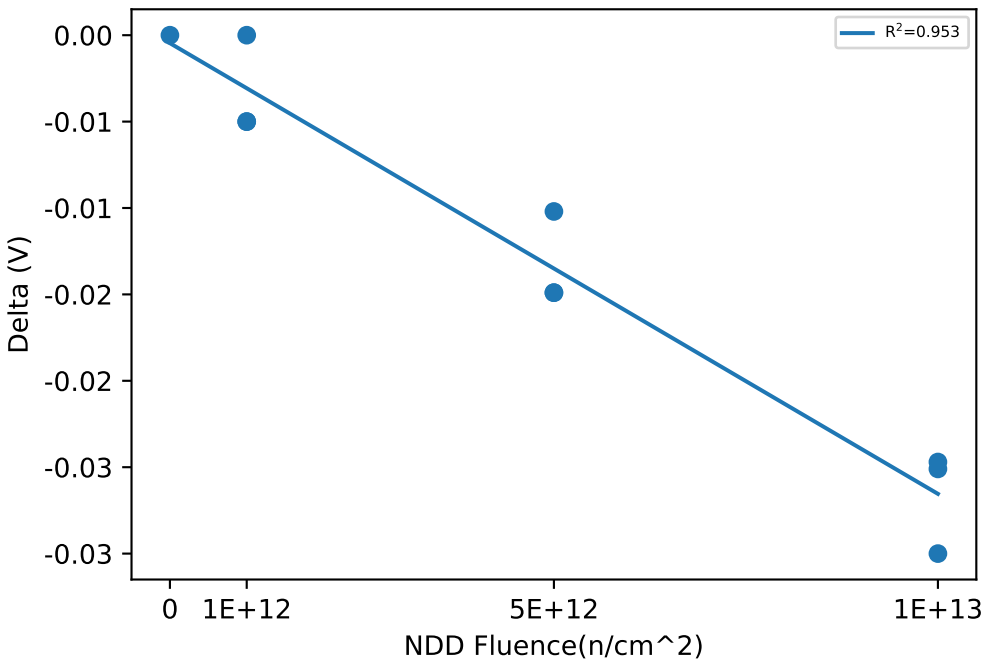
NDD vs Result Stats



Test Results (Lower Limit = 3.8, Upper Limit = 4.3 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.0651	4.0651	0
551	1e+12	NDD	4.0701	4.0651	-0.005
552	1e+12	NDD	4.08	4.075	-0.005
553	5e+12	NDD	4.0599	4.045	-0.0149
554	5e+12	NDD	4.0599	4.045	-0.0149
555	5e+12	NDD	4.0701	4.0599	-0.0102
556	1e+13	NDD	4.08	4.0549	-0.0251
557	1e+13	NDD	4.0599	4.0352	-0.0247
558	1e+13	NDD	4.0849	4.0549	-0.03
559	0	NDD, Ctrl	4.0549	4.0549	0

NDD vs Post - Pre Exposure Delta

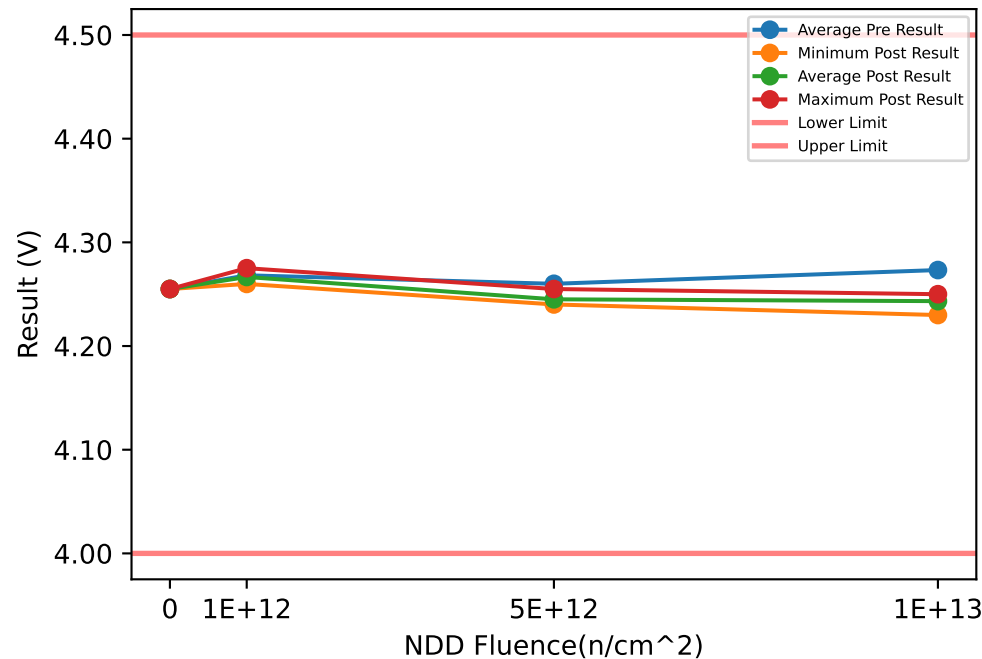


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.0549	4.0549	4.0549		4.0549	4.0549	4.0549		0	0	0	
1e+12	4.0651	4.0717	4.08	0.0075831	4.0651	4.0684	4.075	0.0057158	-0.005	-0.0033333	0	0.0028868
5e+12	4.0599	4.0633	4.0701	0.005889	4.045	4.05	4.0599	0.0086025	-0.0149	-0.013333	-0.0102	0.0027135
1e+13	4.0599	4.0749	4.0849	0.013248	4.0352	4.0483	4.0549	0.011374	-0.03	-0.0266	-0.0247	0.0029513

Device Test: 87.1 V_BP5H_TH_RISE(UVLO BP5H Rise Thresh VIN_14V)

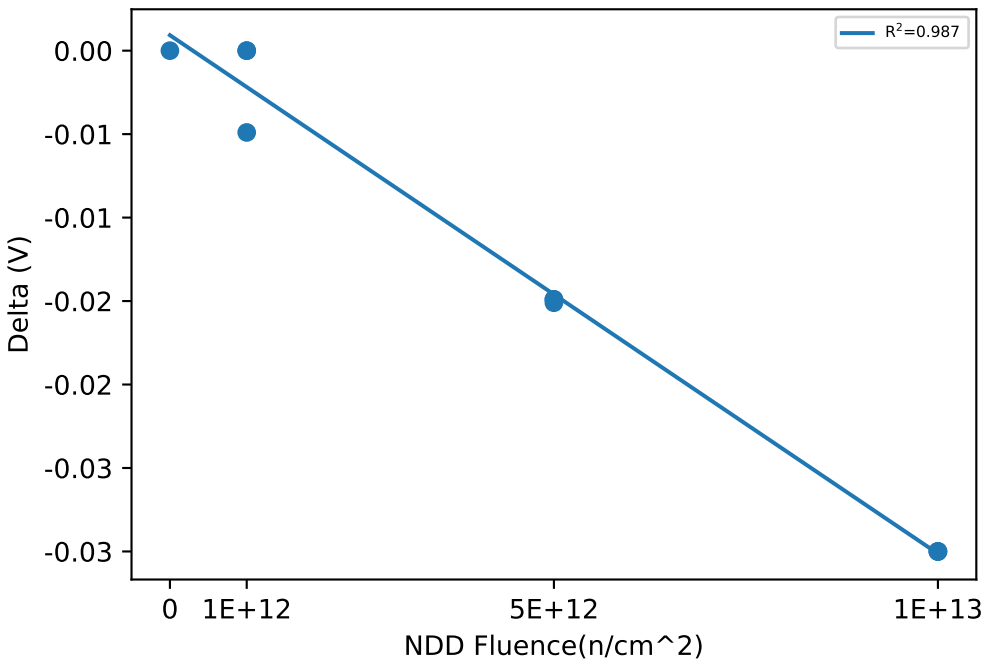
NDD vs Result Stats



Test Results (Lower Limit = 4.0, Upper Limit = 4.5 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.2648	4.2599	-0.0049
551	1e+12	NDD	4.2648	4.2648	0
552	1e+12	NDD	4.2751	4.2751	0
553	5e+12	NDD	4.255	4.2401	-0.0149
554	5e+12	NDD	4.255	4.2401	-0.0149
555	5e+12	NDD	4.2701	4.255	-0.0151
556	1e+13	NDD	4.28	4.25	-0.03
557	1e+13	NDD	4.2599	4.2299	-0.03
558	1e+13	NDD	4.28	4.25	-0.03
559	0	NDD, Ctrl	4.255	4.255	0

NDD vs Post - Pre Exposure Delta

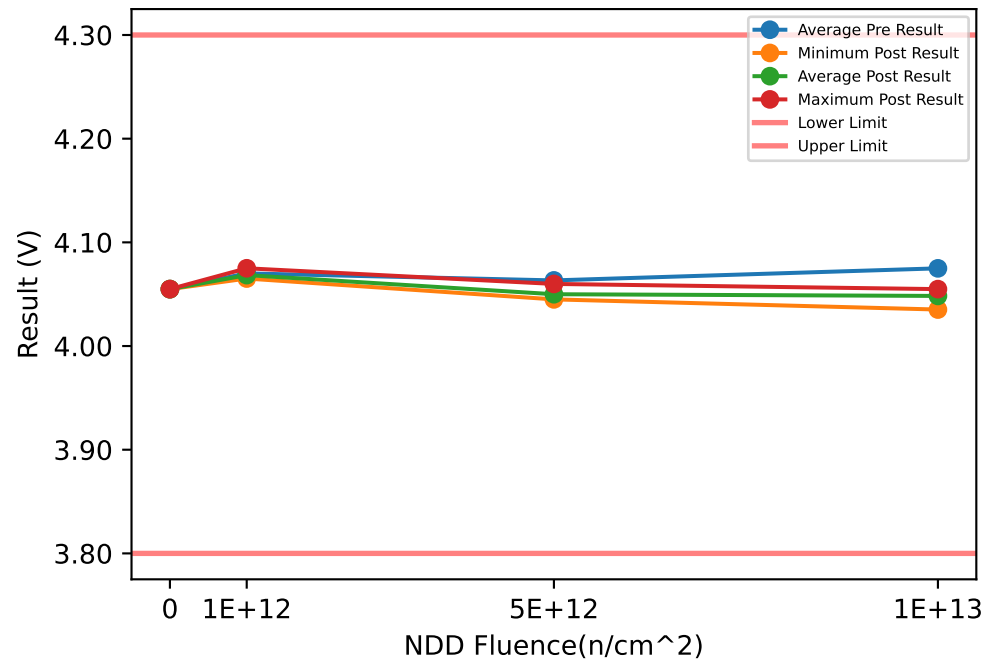


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.255	4.255	4.255		4.255	4.255	4.255		0	0	0	
1e+12	4.2648	4.2682	4.2751	0.0059467	4.2599	4.2666	4.2751	0.0077582	-0.0049	-0.0016333	0	0.002829
5e+12	4.255	4.26	4.2701	0.008718	4.2401	4.2451	4.255	0.0086025	-0.0151	-0.014967	-0.0149	0.00011547
1e+13	4.2599	4.2733	4.28	0.011605	4.2299	4.2433	4.25	0.011605	-0.03	-0.03	-0.03	0

Device Test: 87.2 V_BP5H_TH_FALL(UVLO BP5H Fall Thresh VIN_14V)

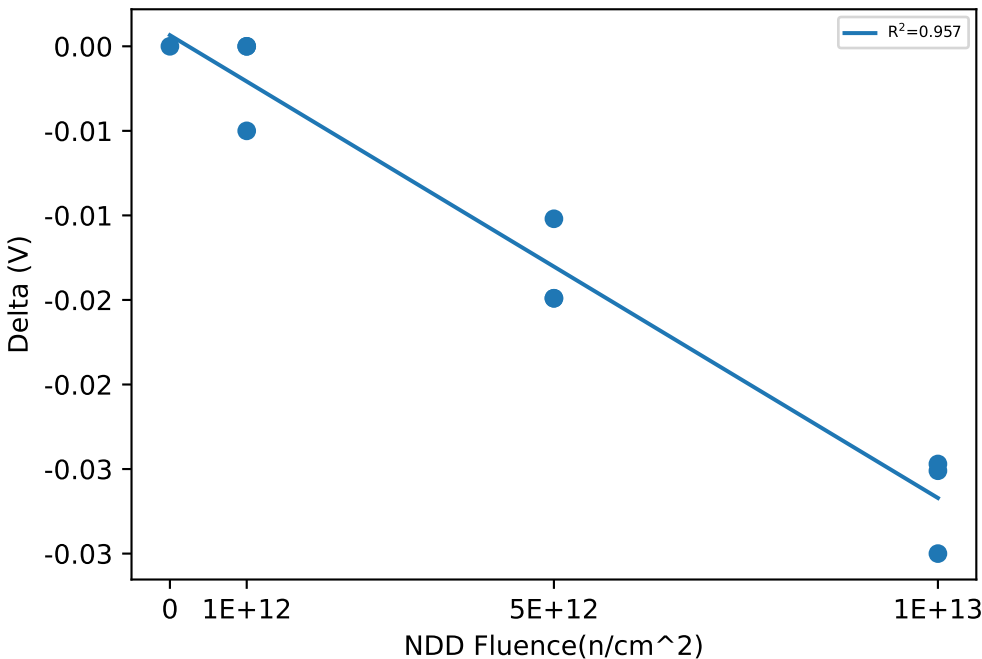
NDD vs Result Stats



Test Results (Lower Limit = 3.8, Upper Limit = 4.3 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	4.0651	4.0651	0
551	1e+12	NDD	4.0701	4.0651	-0.005
552	1e+12	NDD	4.075	4.075	0
553	5e+12	NDD	4.0599	4.045	-0.0149
554	5e+12	NDD	4.0599	4.045	-0.0149
555	5e+12	NDD	4.0701	4.0599	-0.0102
556	1e+13	NDD	4.08	4.0549	-0.0251
557	1e+13	NDD	4.0599	4.0352	-0.0247
558	1e+13	NDD	4.0849	4.0549	-0.03
559	0	NDD, Ctrl	4.0549	4.0549	0

NDD vs Post - Pre Exposure Delta

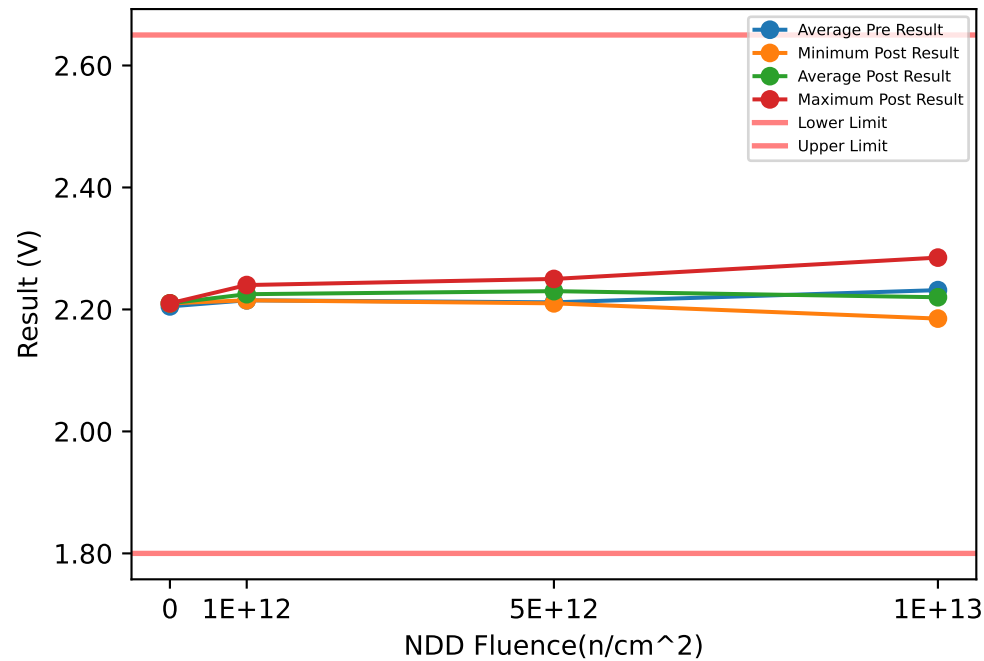


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.0549	4.0549	4.0549		4.0549	4.0549	4.0549		0	0	0	
1e+12	4.0651	4.0701	4.075	0.0049501	4.0651	4.0684	4.075	0.0057158	-0.005	-0.0016667	0	0.0028868
5e+12	4.0599	4.0633	4.0701	0.005889	4.045	4.05	4.0599	0.0086025	-0.0149	-0.013333	-0.0102	0.0027135
1e+13	4.0599	4.0749	4.0849	0.013248	4.0352	4.0483	4.0549	0.011374	-0.03	-0.0266	-0.0247	0.0029513

Device Test: 90.0 V_PWM_LI_IH(PWM_LI Rise Thresh VIN_10V)

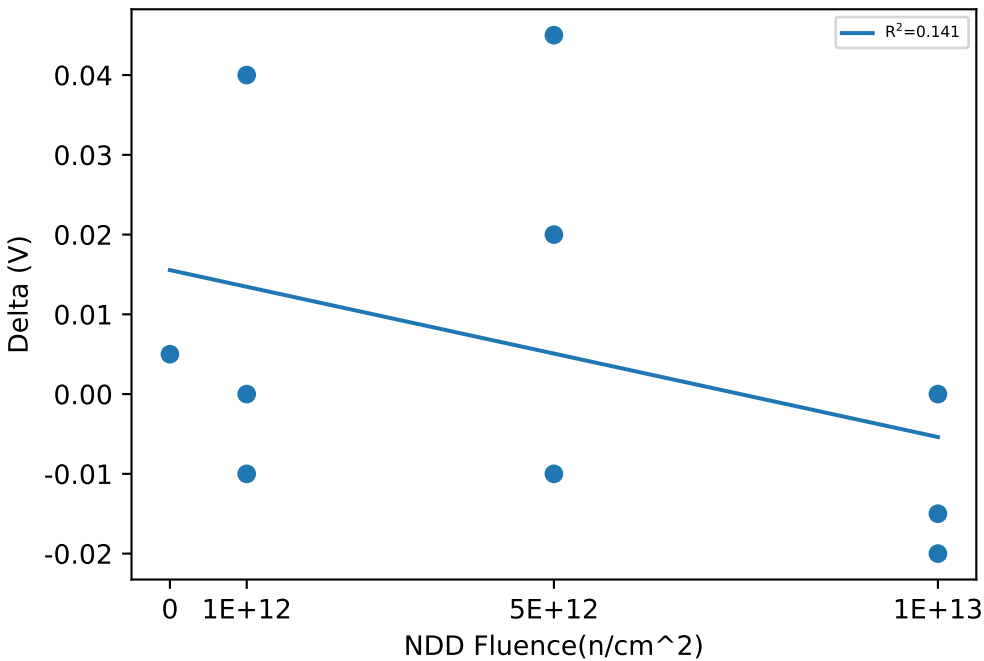
NDD vs Result Stats



Test Results (Lower Limit = 1.8, Upper Limit = 2.65 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	2.225	2.215	-0.01
551	1e+12	NDD	2.22	2.22	0
552	1e+12	NDD	2.2	2.24	0.04
553	5e+12	NDD	2.23	2.25	0.02
554	5e+12	NDD	2.185	2.23	0.045
555	5e+12	NDD	2.22	2.21	-0.01
556	1e+13	NDD	2.205	2.19	-0.015
557	1e+13	NDD	2.205	2.185	-0.02
558	1e+13	NDD	2.285	2.285	0
559	0	NDD, Ctrl	2.205	2.21	0.005

NDD vs Post - Pre Exposure Delta

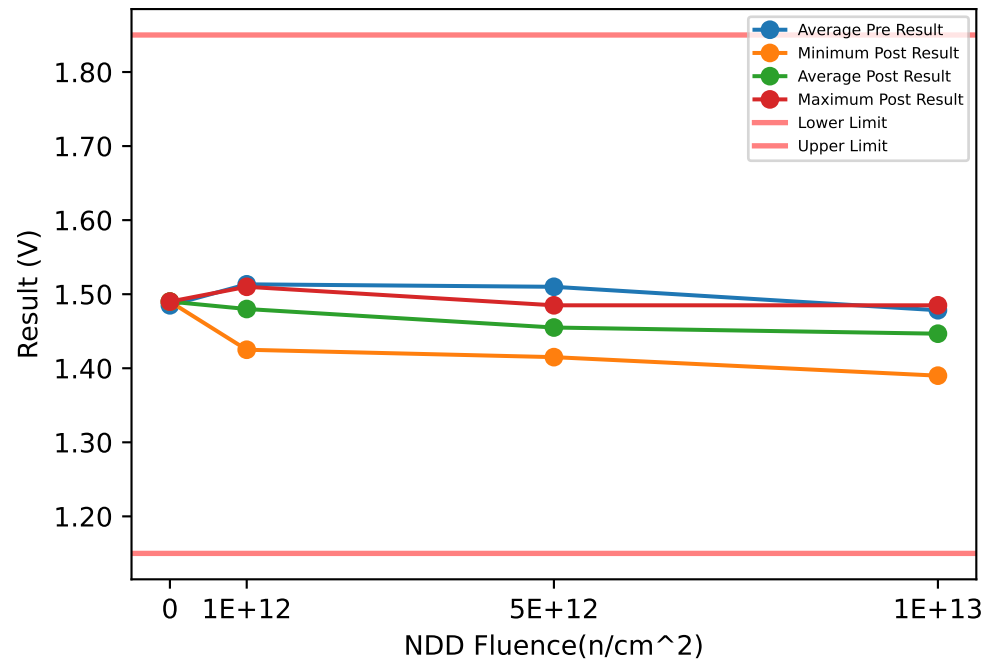


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.205	2.205	2.205		2.21	2.21	2.21		0.005	0.005	0.005	
1e+12	2.2	2.215	2.225	0.013229	2.215	2.225	2.24	0.013229	-0.01	0.01	0.04	0.026458
5e+12	2.185	2.2117	2.23	0.023629	2.21	2.23	2.25	0.02	-0.01	0.018333	0.045	0.027538
1e+13	2.205	2.2317	2.285	0.046188	2.185	2.22	2.285	0.056347	-0.02	-0.011667	0	0.010408

Device Test: 90.1 V_PWM_LI_IL(PWM_LI Fall Thresh VIN_10V)

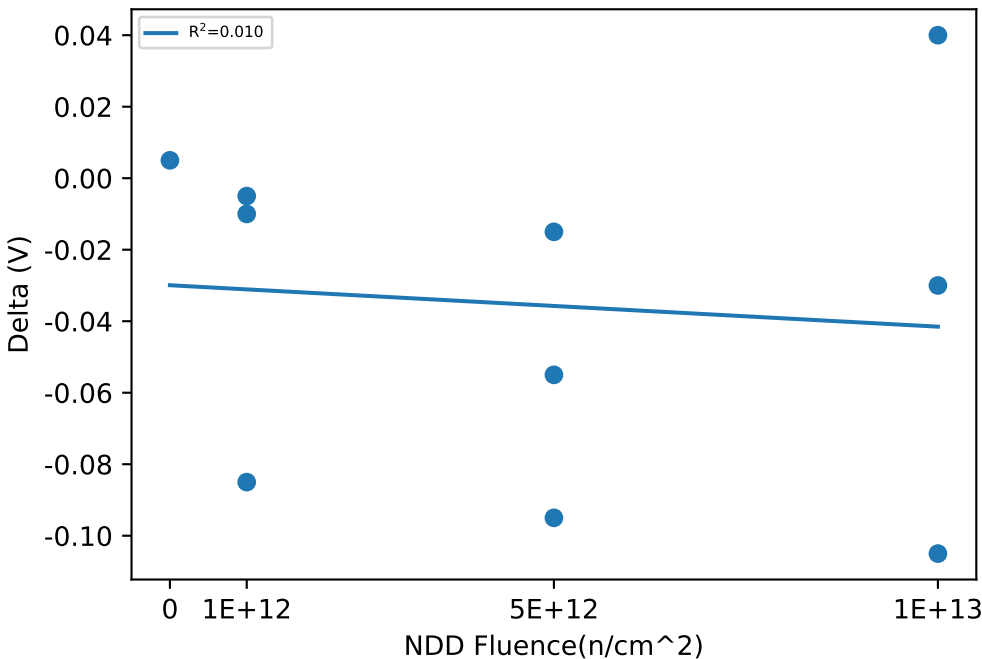
NDD vs Result Stats



Test Results (Lower Limit = 1.15, Upper Limit = 1.85 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	1.51	1.425	-0.085
551	1e+12	NDD	1.515	1.51	-0.005
552	1e+12	NDD	1.515	1.505	-0.01
553	5e+12	NDD	1.51	1.415	-0.095
554	5e+12	NDD	1.5	1.485	-0.015
555	5e+12	NDD	1.52	1.465	-0.055
556	1e+13	NDD	1.445	1.485	0.04
557	1e+13	NDD	1.495	1.465	-0.03
558	1e+13	NDD	1.495	1.39	-0.105
559	0	NDD, Ctrl	1.485	1.49	0.005

NDD vs Post - Pre Exposure Delta

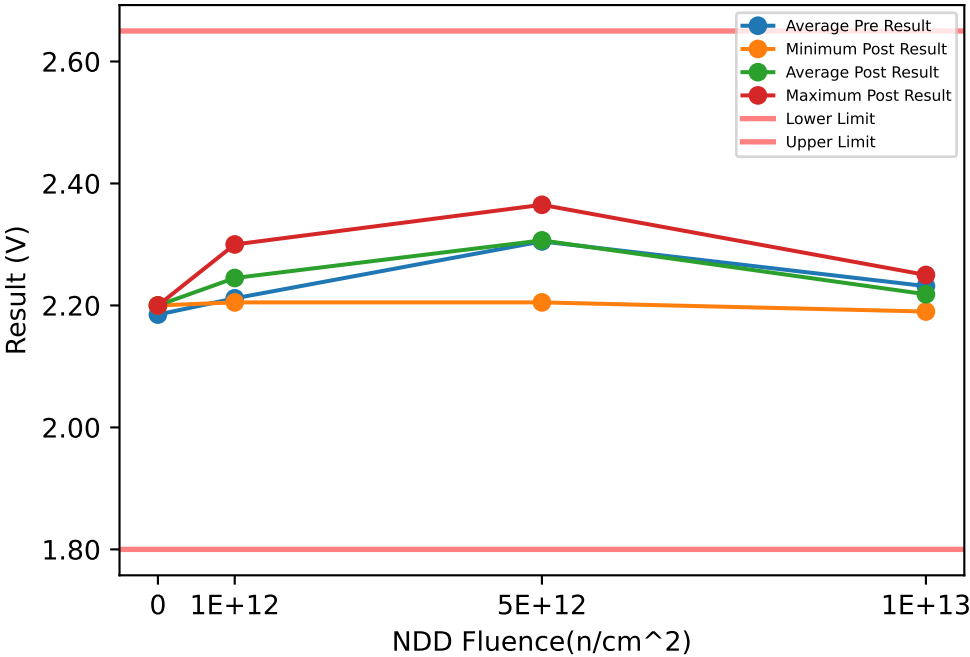


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.485	1.485	1.485		1.49	1.49	1.49		0.005	0.005	0.005	
1e+12	1.51	1.5133	1.515	0.0028868	1.425	1.48	1.51	0.047697	-0.085	-0.033333	-0.005	0.044814
5e+12	1.5	1.51	1.52	0.01	1.415	1.455	1.485	0.036056	-0.095	-0.055	-0.015	0.04
1e+13	1.445	1.4783	1.495	0.028868	1.39	1.4467	1.485	0.050083	-0.105	-0.031667	0.04	0.072514

Device Test: 90.3 V_EN_HI_IH(EN_HI Rise Thresh VIN_10V)

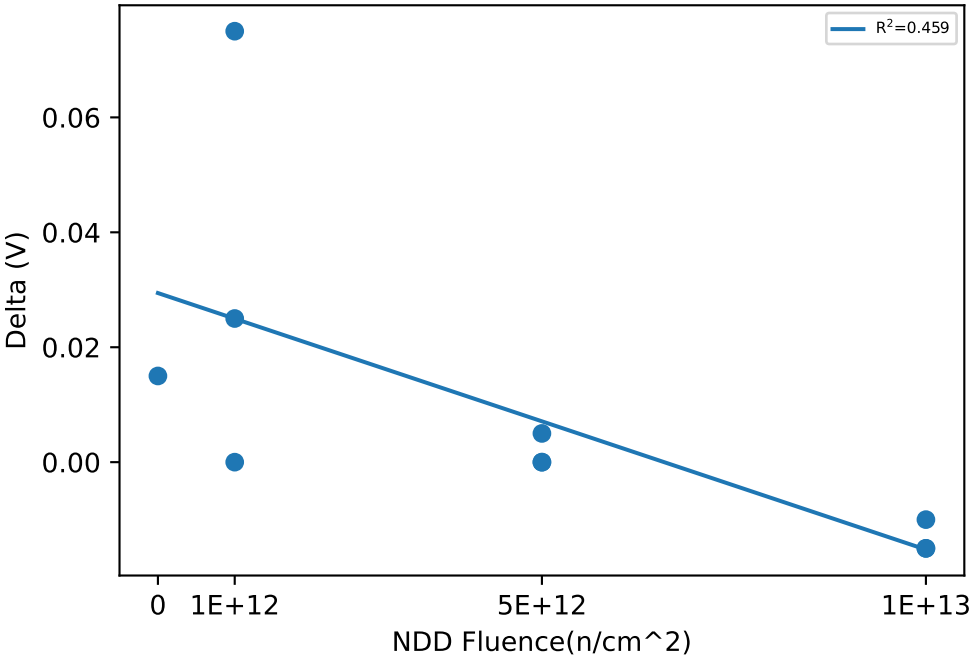
NDD vs Result Stats



Test Results (Lower Limit = 1.8, Upper Limit = 2.65 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	2.225	2.3	0.075
551	1e+12	NDD	2.205	2.23	0.025
552	1e+12	NDD	2.205	2.205	0
553	5e+12	NDD	2.345	2.35	0.005
554	5e+12	NDD	2.365	2.365	0
555	5e+12	NDD	2.205	2.205	0
556	1e+13	NDD	2.265	2.25	-0.015
557	1e+13	NDD	2.205	2.19	-0.015
558	1e+13	NDD	2.225	2.215	-0.01
559	0	NDD, Ctrl	2.185	2.2	0.015

NDD vs Post - Pre Exposure Delta

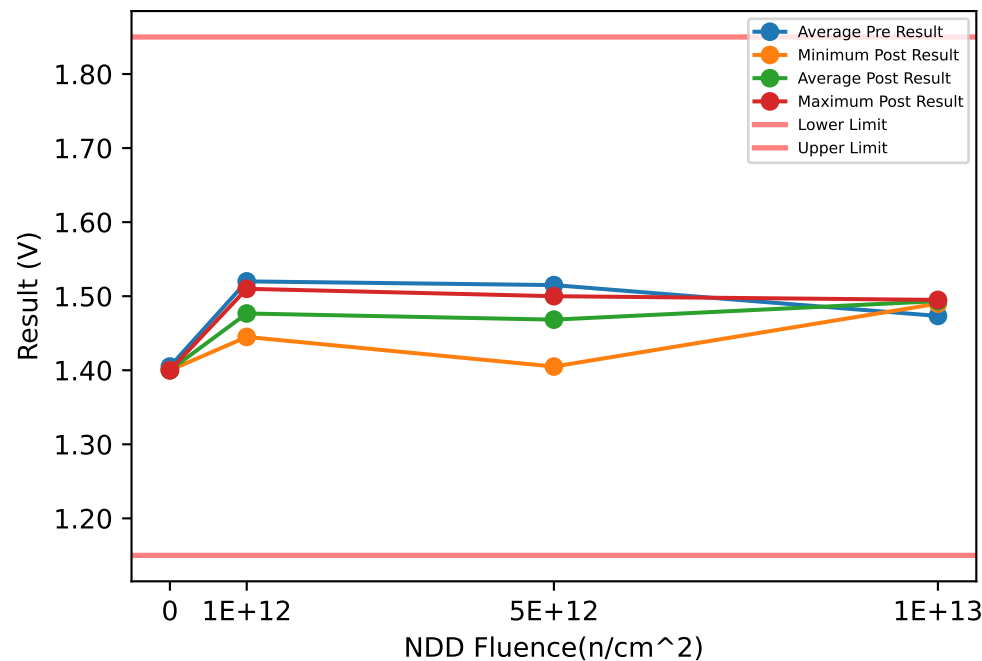


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.185	2.185	2.185		2.2	2.2	2.2		0.015	0.015	0.015	
1e+12	2.205	2.2117	2.225	0.011547	2.205	2.245	2.3	0.049244	0	0.033333	0.075	0.038188
5e+12	2.205	2.305	2.365	0.087178	2.205	2.3067	2.365	0.088365	0	0.0016667	0.005	0.0028868
1e+13	2.205	2.2317	2.265	0.030551	2.19	2.2183	2.25	0.030139	-0.015	-0.013333	-0.01	0.0028868

Device Test: 90.4 V_EN_HI_IL(EN_HI Fall Thresh VIN_10V)

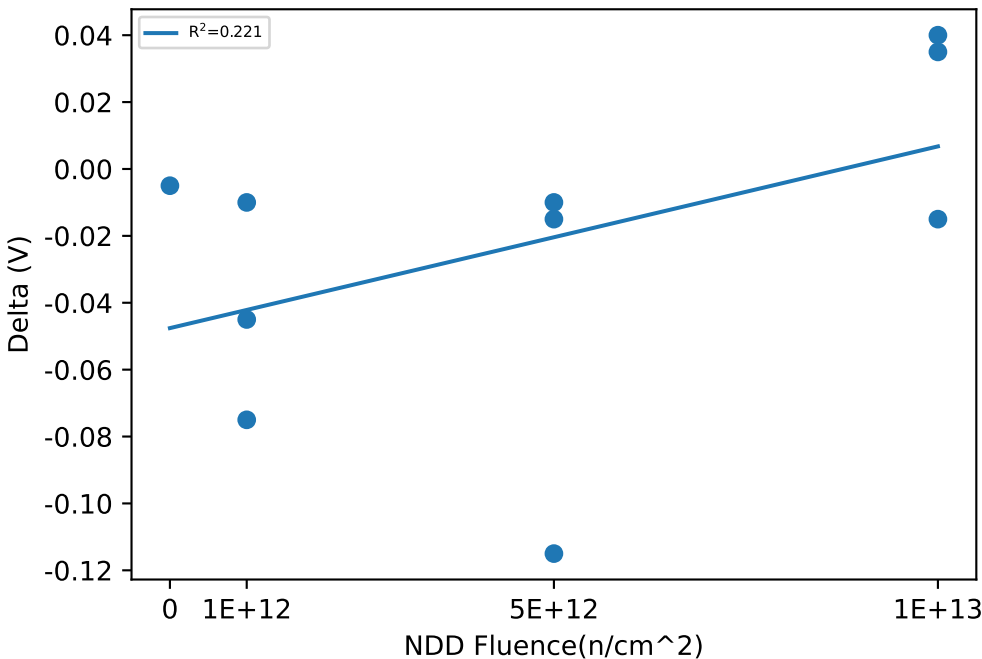
NDD vs Result Stats



Test Results (Lower Limit = 1.15, Upper Limit = 1.85 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	1.52	1.51	-0.01
551	1e+12	NDD	1.52	1.475	-0.045
552	1e+12	NDD	1.52	1.445	-0.075
553	5e+12	NDD	1.52	1.405	-0.115
554	5e+12	NDD	1.51	1.5	-0.01
555	5e+12	NDD	1.515	1.5	-0.015
556	1e+13	NDD	1.45	1.49	0.04
557	1e+13	NDD	1.46	1.495	0.035
558	1e+13	NDD	1.51	1.495	-0.015
559	0	NDD, Ctrl	1.405	1.4	-0.005

NDD vs Post - Pre Exposure Delta

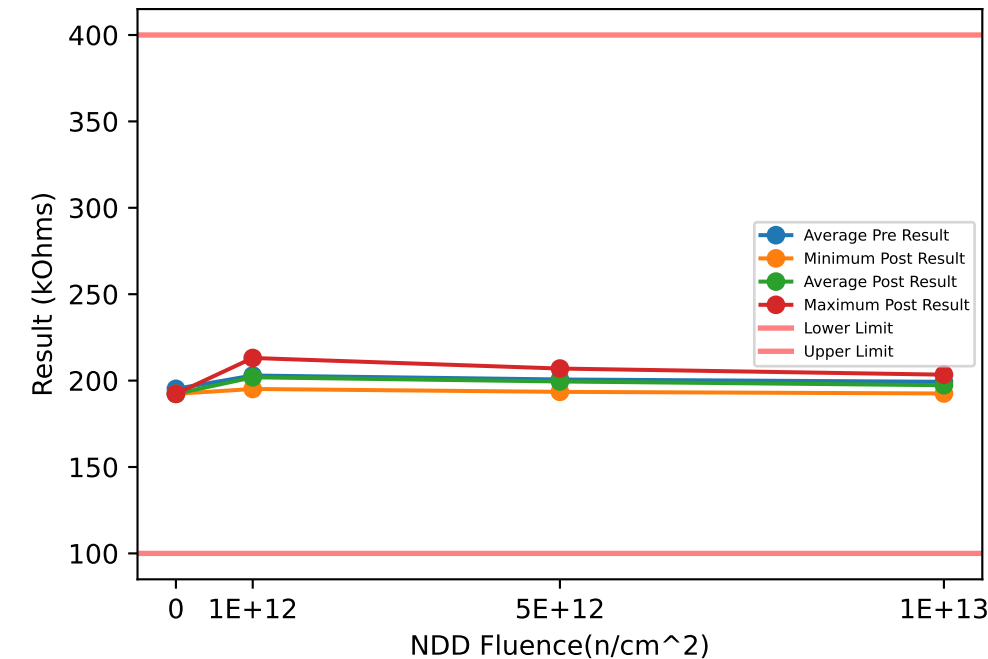


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.405	1.405	1.405		1.4	1.4	1.4		-0.005	-0.005	-0.005	
1e+12	1.52	1.52	1.52	0	1.445	1.4767	1.51	0.032532	-0.075	-0.043333	-0.01	0.032532
5e+12	1.51	1.515	1.52	0.005	1.405	1.4683	1.5	0.054848	-0.115	-0.046667	-0.01	0.059231
1e+13	1.45	1.4733	1.51	0.032146	1.49	1.4933	1.495	0.0028868	-0.015	0.02	0.04	0.030414

Device Test: 90.6 R_PWM_LI_PD(PWM_LI Pull Down Resistance VIN_10V)

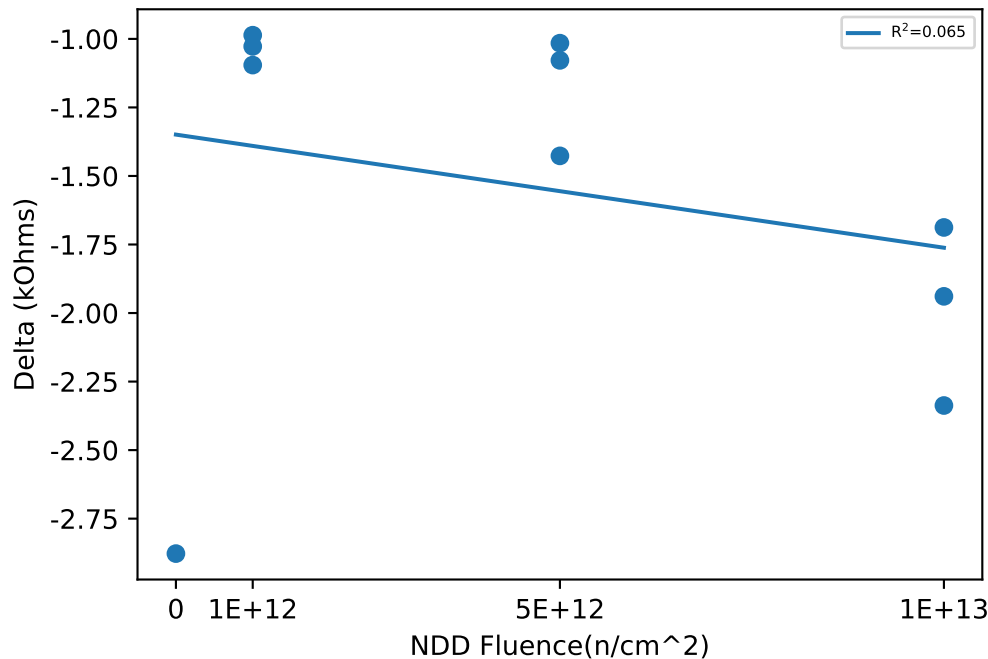
NDD vs Result Stats



Test Results (Lower Limit = 100.0, Upper Limit = 400.0 (kOhms))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	196.14	195.15	-0.9865
551	1e+12	NDD	214.19	213.09	-1.0955
552	1e+12	NDD	198.49	197.46	-1.0273
553	5e+12	NDD	199.41	197.99	-1.4267
554	5e+12	NDD	194.5	193.49	-1.0156
555	5e+12	NDD	208.05	206.97	-1.0783
556	1e+13	NDD	205.12	203.43	-1.6878
557	1e+13	NDD	197.91	195.97	-1.9391
558	1e+13	NDD	194.88	192.55	-2.3373
559	0	NDD, Ctrl	195.22	192.35	-2.8775

NDD vs Post - Pre Exposure Delta

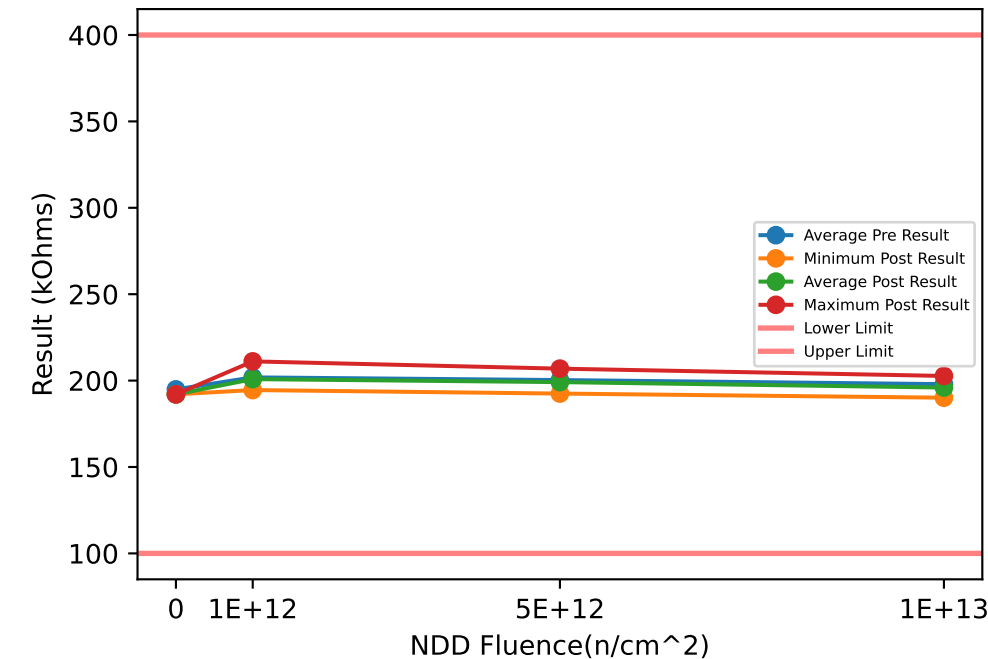


Test Statistics (kOhms)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	195.22	195.22	195.22		192.35	192.35	192.35		-2.8775	-2.8775	-2.8775	
1e+12	196.14	202.94	214.19	9.812	195.15	201.9	213.09	9.7588	-1.0955	-1.0364	-0.9865	0.055071
5e+12	194.5	200.66	208.05	6.859	193.49	199.48	206.97	6.866	-1.4267	-1.1735	-1.0156	0.22148
1e+13	194.88	199.3	205.12	5.2576	192.55	197.32	203.43	5.5652	-2.3373	-1.9881	-1.6878	0.32751

Device Test: 90.7 R_EN_HI_PD(EN_HI Pull Down Resistance VIN_10V)

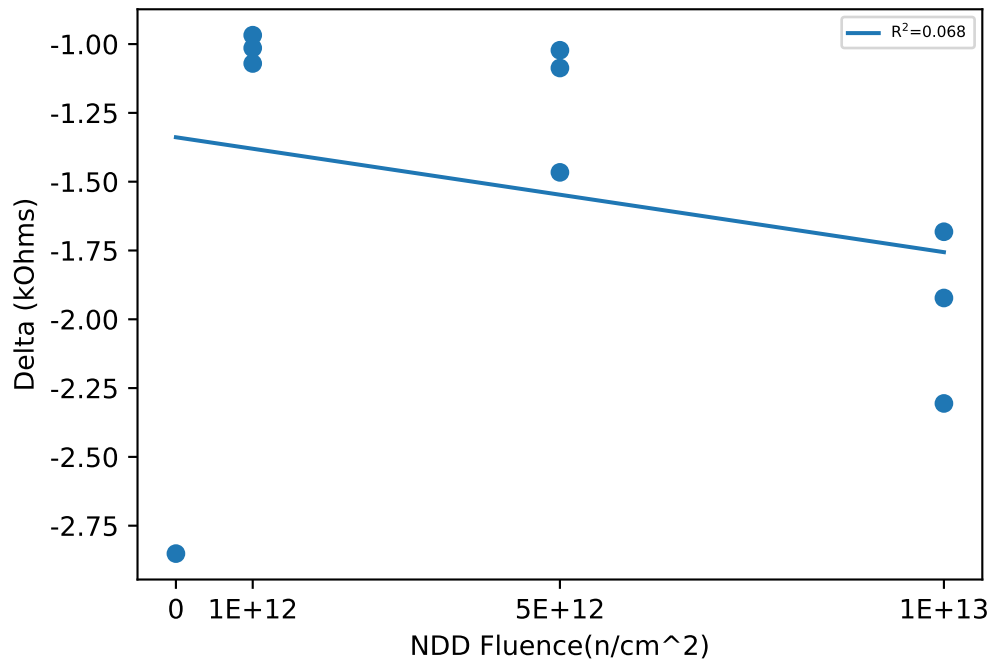
NDD vs Result Stats



Test Results (Lower Limit = 100.0, Upper Limit = 400.0 (kOhms))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	195.49	194.53	-0.9677
551	1e+12	NDD	212.19	211.12	-1.0705
552	1e+12	NDD	197.91	196.89	-1.0142
553	5e+12	NDD	199.42	197.96	-1.4661
554	5e+12	NDD	193.51	192.49	-1.0224
555	5e+12	NDD	208	206.92	-1.0869
556	1e+13	NDD	204.38	202.69	-1.6819
557	1e+13	NDD	197.03	195.11	-1.9226
558	1e+13	NDD	192.42	190.11	-2.3058
559	0	NDD, Ctrl	194.91	192.06	-2.8514

NDD vs Post - Pre Exposure Delta

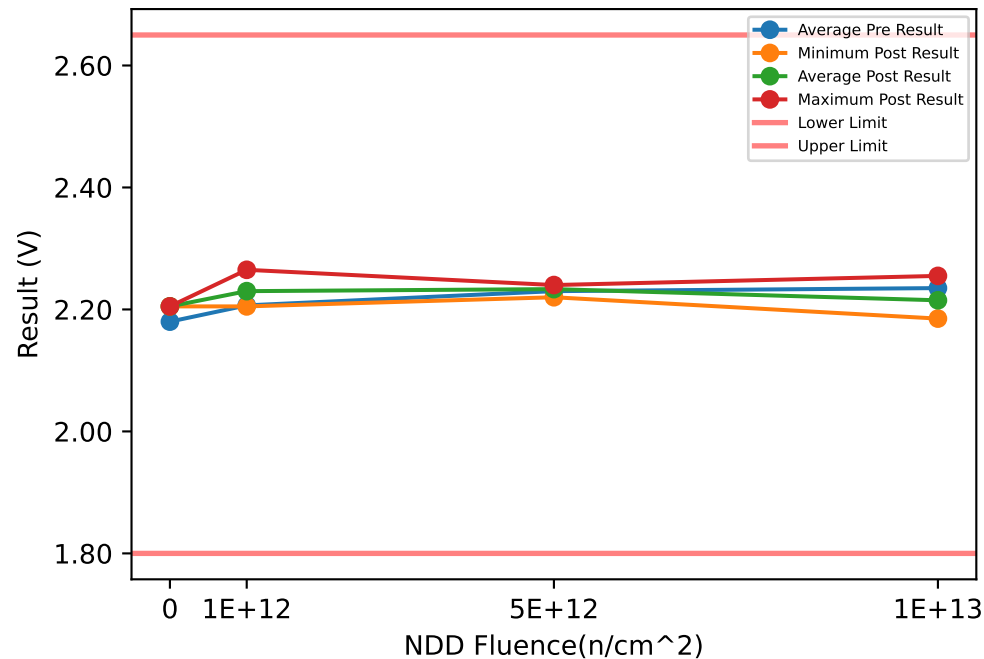


Test Statistics (kOhms)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	194.91	194.91	194.91		192.06	192.06	192.06		-2.8514	-2.8514	-2.8514	
1e+12	195.49	201.86	212.19	9.0227	194.53	200.85	211.12	8.9741	-1.0705	-1.0175	-0.9677	0.051478
5e+12	193.51	200.31	208	7.2858	192.49	199.12	206.92	7.2828	-1.4661	-1.1918	-1.0224	0.23973
1e+13	192.42	197.94	204.38	6.0313	190.11	195.97	202.69	6.3357	-2.3058	-1.9701	-1.6819	0.31465

Device Test: 91.0 V_PWM_LI_IH(PWM_LI Rise Thresh VIN_12V)

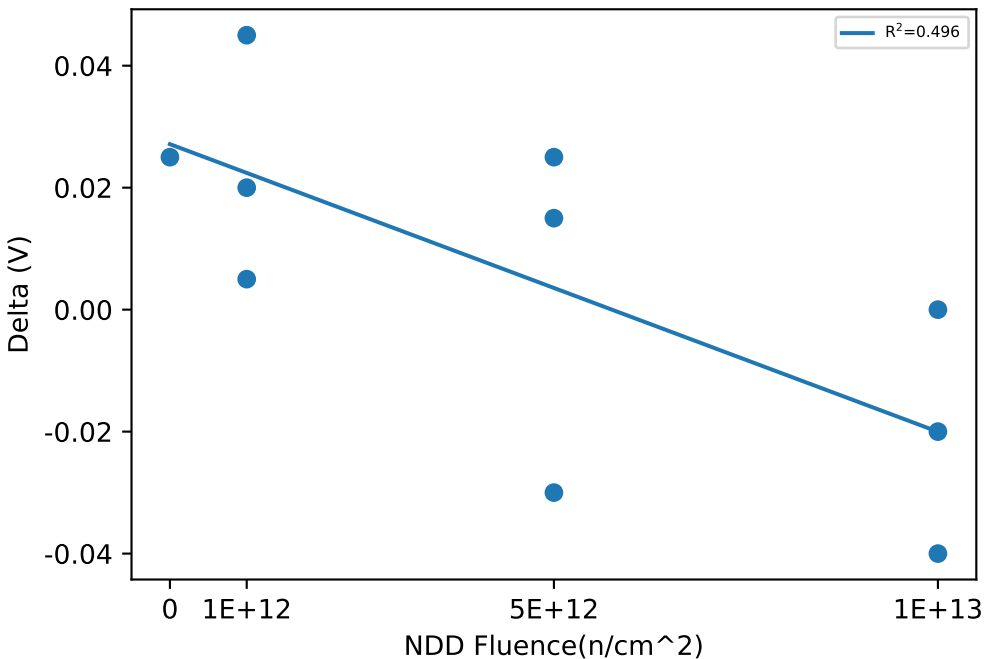
NDD vs Result Stats



Test Results (Lower Limit = 1.8, Upper Limit = 2.65 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	2.2	2.22	0.02
551	1e+12	NDD	2.22	2.265	0.045
552	1e+12	NDD	2.2	2.205	0.005
553	5e+12	NDD	2.27	2.24	-0.03
554	5e+12	NDD	2.205	2.22	0.015
555	5e+12	NDD	2.215	2.24	0.025
556	1e+13	NDD	2.205	2.205	0
557	1e+13	NDD	2.205	2.185	-0.02
558	1e+13	NDD	2.295	2.255	-0.04
559	0	NDD, Ctrl	2.18	2.205	0.025

NDD vs Post - Pre Exposure Delta

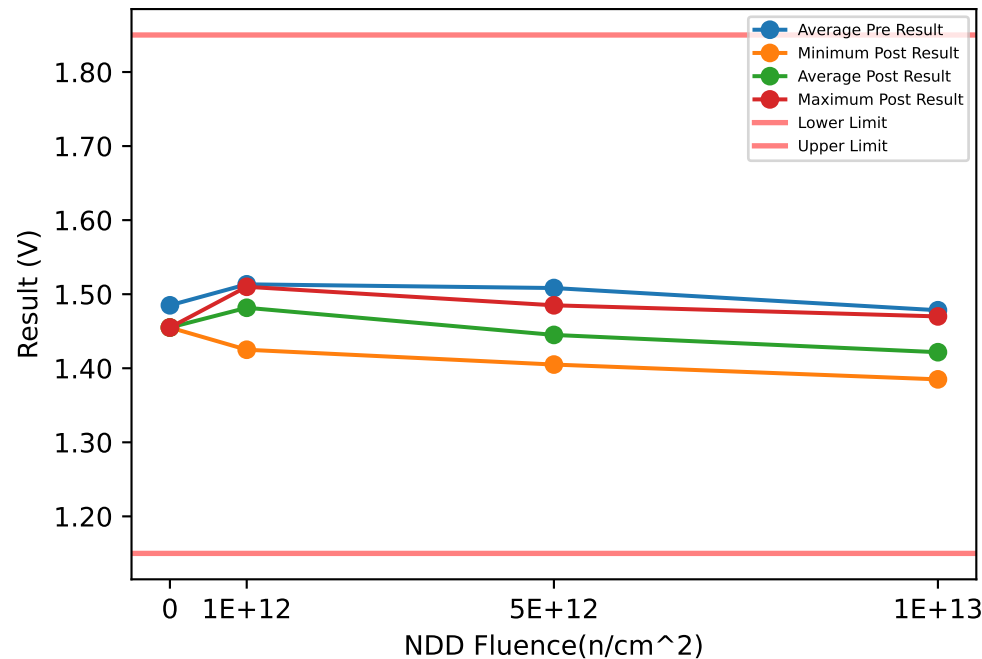


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.18	2.18	2.18		2.205	2.205	2.205		0.025	0.025	0.025	
1e+12	2.2	2.2067	2.22	0.011547	2.205	2.23	2.265	0.031225	0.005	0.023333	0.045	0.020207
5e+12	2.205	2.23	2.27	0.035	2.22	2.2333	2.24	0.011547	-0.03	0.0033333	0.025	0.029297
1e+13	2.205	2.235	2.295	0.051962	2.185	2.215	2.255	0.036056	-0.04	-0.02	0	0.02

Device Test: 91.1 V_PWM_LI_IL(PWM_LI Fall Thresh VIN_12V)

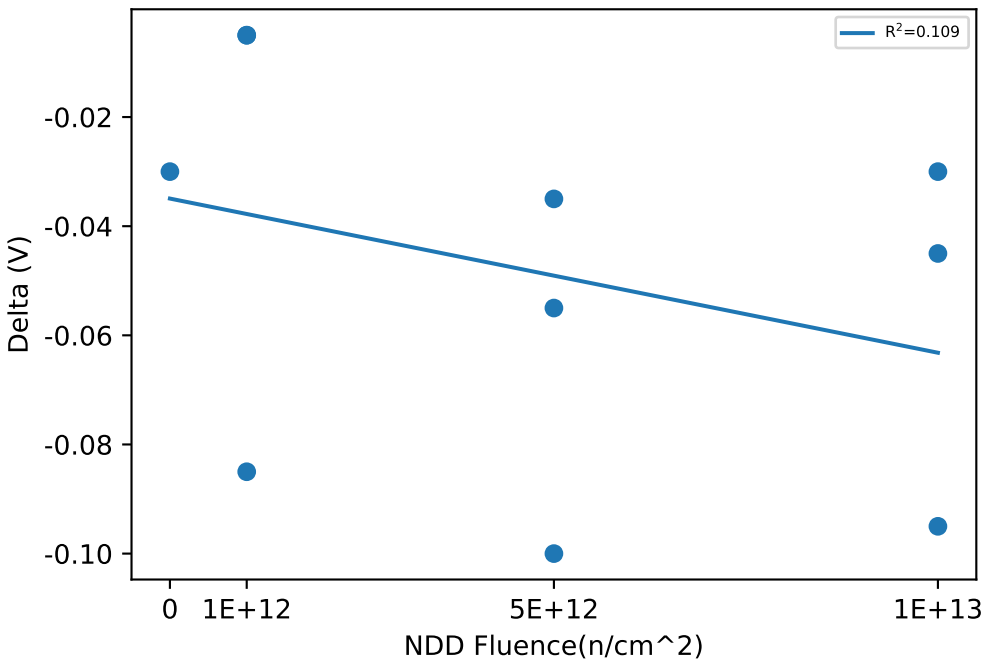
NDD vs Result Stats



Test Results (Lower Limit = 1.15, Upper Limit = 1.85 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	1.51	1.425	-0.085
551	1e+12	NDD	1.515	1.51	-0.005
552	1e+12	NDD	1.515	1.51	-0.005
553	5e+12	NDD	1.505	1.405	-0.1
554	5e+12	NDD	1.5	1.445	-0.055
555	5e+12	NDD	1.52	1.485	-0.035
556	1e+13	NDD	1.5	1.47	-0.03
557	1e+13	NDD	1.505	1.41	-0.095
558	1e+13	NDD	1.43	1.385	-0.045
559	0	NDD, Ctrl	1.485	1.455	-0.03

NDD vs Post - Pre Exposure Delta

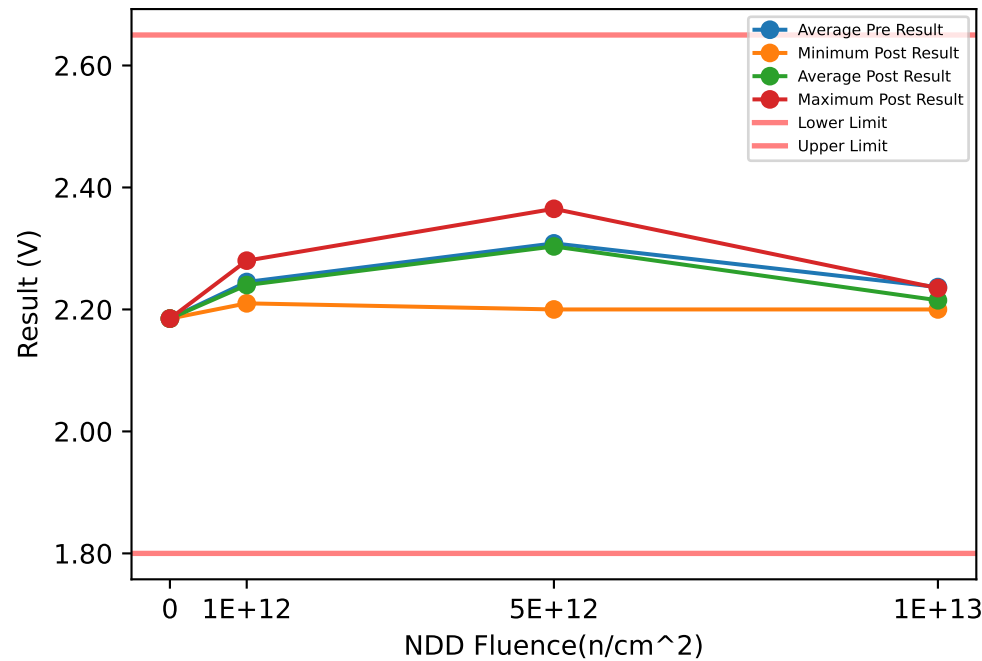


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.485	1.485	1.485		1.455	1.455	1.455		-0.03	-0.03	-0.03	
1e+12	1.51	1.5133	1.515	0.0028868	1.425	1.4817	1.51	0.049075	-0.085	-0.031667	-0.005	0.046188
5e+12	1.5	1.5083	1.52	0.010408	1.405	1.445	1.485	0.04	-0.1	-0.063333	-0.035	0.033292
1e+13	1.43	1.4783	1.505	0.041932	1.385	1.4217	1.47	0.043684	-0.095	-0.056667	-0.03	0.034034

Device Test: 91.3 V_EN_HI_IH(EN_HI Rise Thresh VIN_12V)

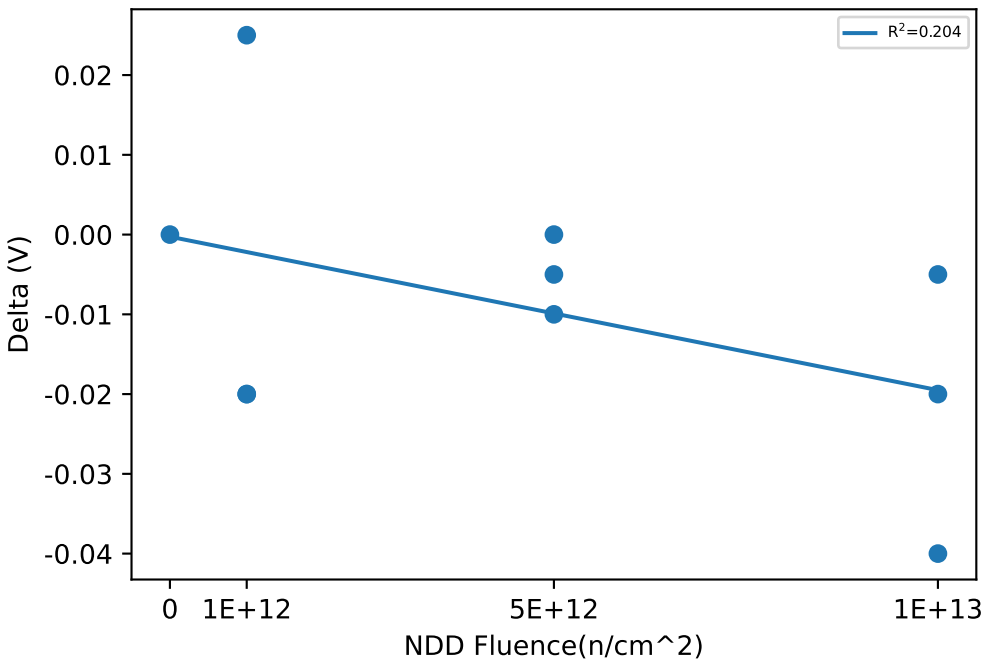
NDD vs Result Stats



Test Results (Lower Limit = 1.8, Upper Limit = 2.65 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	2.3	2.28	-0.02
551	1e+12	NDD	2.23	2.21	-0.02
552	1e+12	NDD	2.205	2.23	0.025
553	5e+12	NDD	2.345	2.345	0
554	5e+12	NDD	2.375	2.365	-0.01
555	5e+12	NDD	2.205	2.2	-0.005
556	1e+13	NDD	2.275	2.235	-0.04
557	1e+13	NDD	2.205	2.2	-0.005
558	1e+13	NDD	2.23	2.21	-0.02
559	0	NDD, Ctrl	2.185	2.185	0

NDD vs Post - Pre Exposure Delta

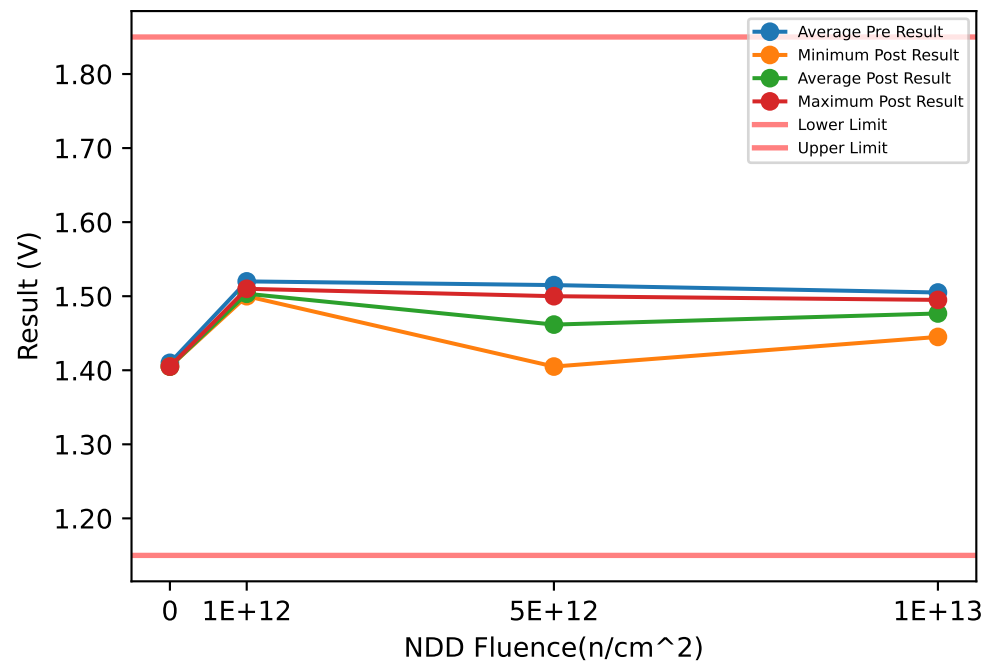


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.185	2.185	2.185		2.185	2.185	2.185		0	0	0	
1e+12	2.205	2.245	2.3	0.049244	2.21	2.24	2.28	0.036056	-0.02	-0.005	0.025	0.025981
5e+12	2.205	2.3083	2.375	0.090738	2.2	2.3033	2.365	0.090046	-0.01	-0.005	0	0.005
1e+13	2.205	2.2367	2.275	0.035473	2.2	2.215	2.235	0.018028	-0.04	-0.021667	-0.005	0.017559

Device Test: 91.4 V_EN_HI_IL(EN_HI Fall Thresh VIN_12V)

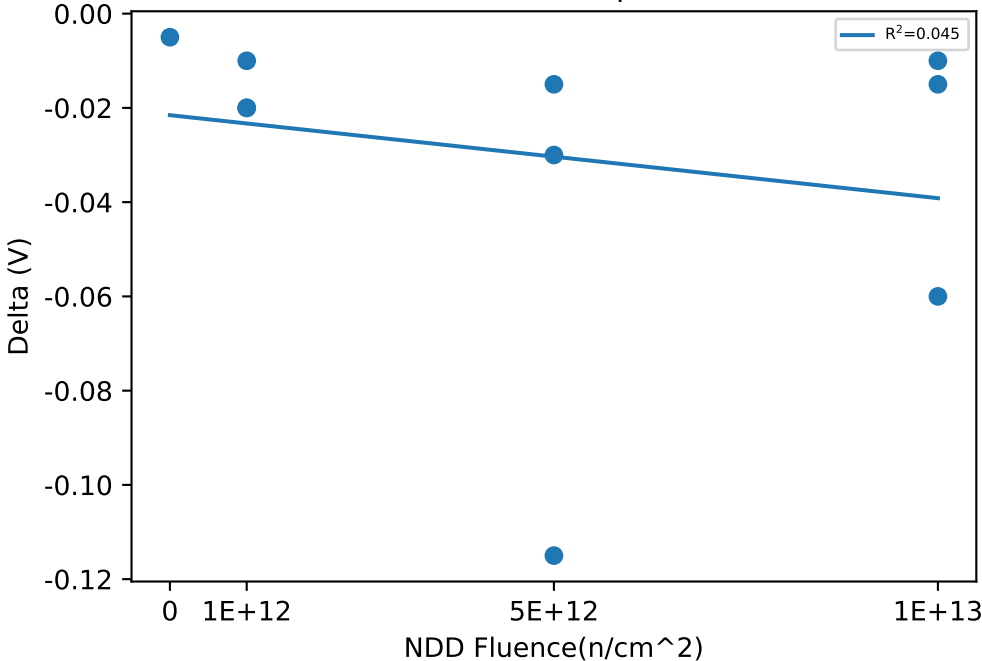
NDD vs Result Stats



Test Results (Lower Limit = 1.15, Upper Limit = 1.85 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	1.52	1.51	-0.01
551	1e+12	NDD	1.52	1.5	-0.02
552	1e+12	NDD	1.52	1.5	-0.02
553	5e+12	NDD	1.52	1.405	-0.115
554	5e+12	NDD	1.51	1.48	-0.03
555	5e+12	NDD	1.515	1.5	-0.015
556	1e+13	NDD	1.5	1.49	-0.01
557	1e+13	NDD	1.505	1.445	-0.06
558	1e+13	NDD	1.51	1.495	-0.015
559	0	NDD, Ctrl	1.41	1.405	-0.005

NDD vs Post - Pre Exposure Delta

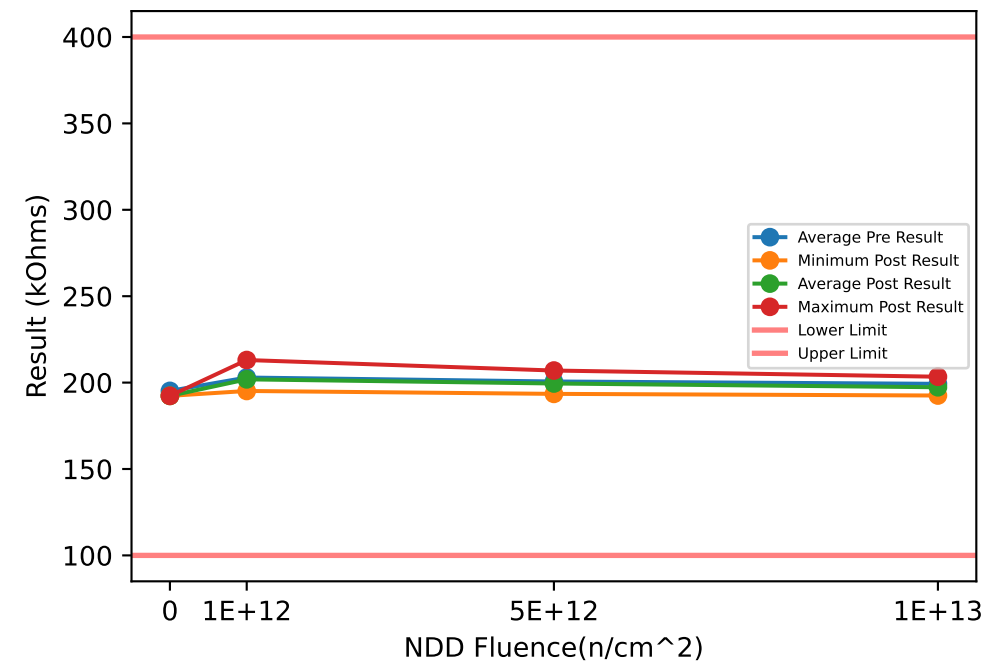


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.41	1.41	1.41		1.405	1.405	1.405		-0.005	-0.005	-0.005	
1e+12	1.52	1.52	1.52	0	1.5	1.5033	1.51	0.0057735	-0.02	-0.016667	-0.01	0.0057735
5e+12	1.51	1.515	1.52	0.005	1.405	1.4617	1.5	0.050083	-0.115	-0.053333	-0.015	0.053929
1e+13	1.5	1.505	1.51	0.005	1.445	1.4767	1.495	0.027538	-0.06	-0.028333	-0.01	0.027538

Device Test: 91.6 R_PWM_LI_PD(PWM_LI Pull Down Resistance VIN_12V)

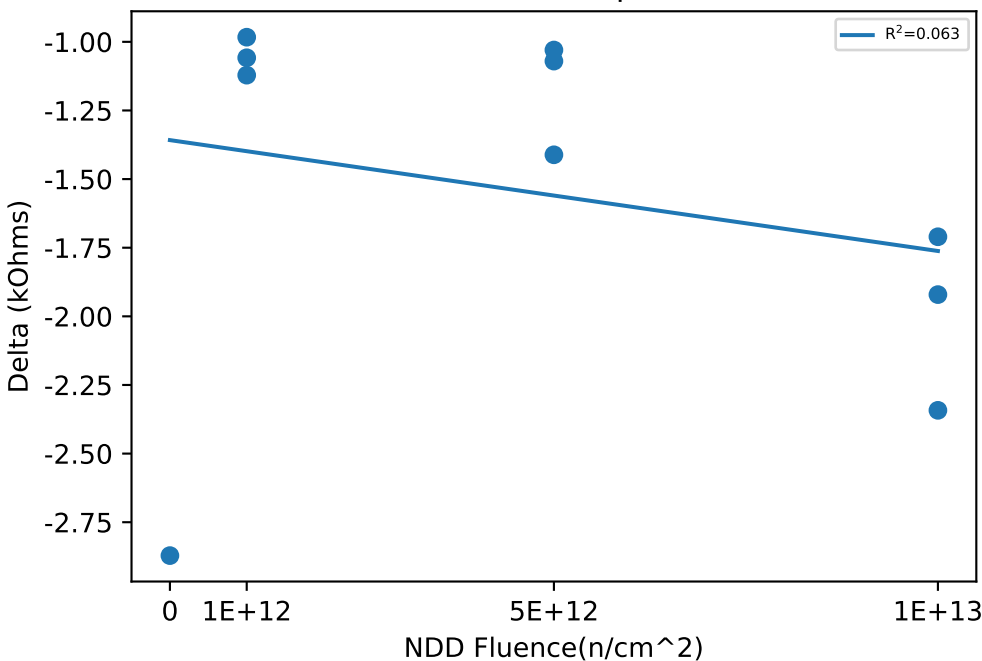
NDD vs Result Stats



Test Results (Lower Limit = 100.0, Upper Limit = 400.0 (kOhms))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	196.14	195.16	-0.9831
551	1e+12	NDD	214.18	213.06	-1.1214
552	1e+12	NDD	198.48	197.42	-1.058
553	5e+12	NDD	199.39	197.98	-1.4115
554	5e+12	NDD	194.51	193.48	-1.0298
555	5e+12	NDD	208.05	206.98	-1.0702
556	1e+13	NDD	205.11	203.4	-1.7101
557	1e+13	NDD	197.9	195.98	-1.9208
558	1e+13	NDD	194.87	192.52	-2.3424
559	0	NDD, Ctrl	195.2	192.33	-2.8716

NDD vs Post - Pre Exposure Delta

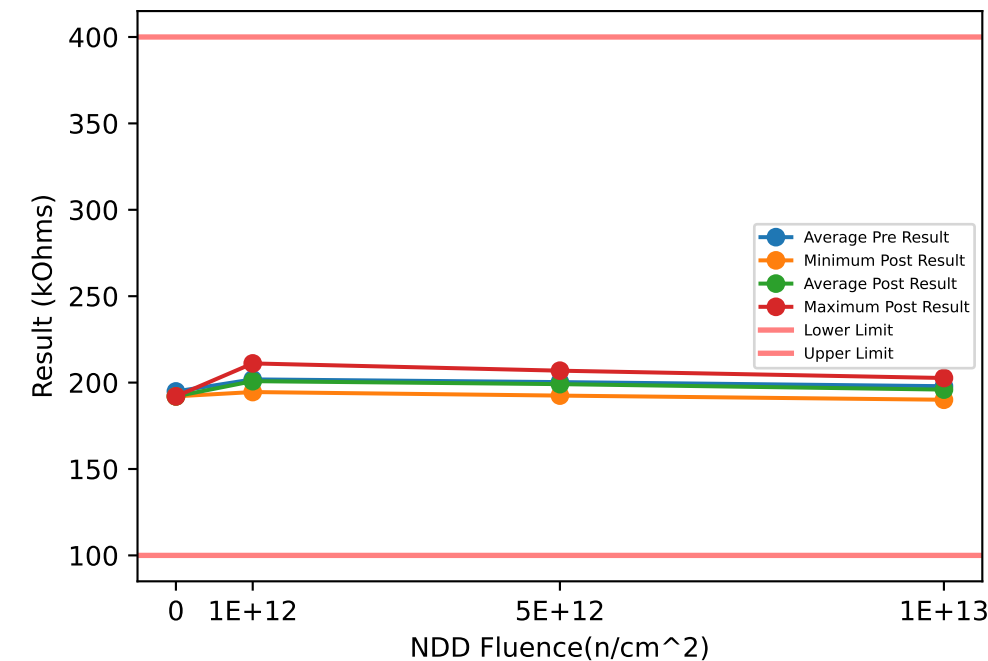


Test Statistics (kOhms)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	195.2	195.2	195.2		192.33	192.33	192.33		-2.8716	-2.8716	-2.8716	
1e+12	196.14	202.93	214.18	9.813	195.16	201.88	213.06	9.7508	-1.1214	-1.0542	-0.9831	0.06923
5e+12	194.51	200.65	208.05	6.8606	193.48	199.48	206.98	6.877	-1.4115	-1.1705	-1.0298	0.20969
1e+13	194.87	199.29	205.11	5.2637	192.52	197.3	203.4	5.559	-2.3424	-1.9911	-1.7101	0.32196

Device Test: 91.7 R_EN_HI_PD(EN_HI Pull Down Resistance VIN_12V)

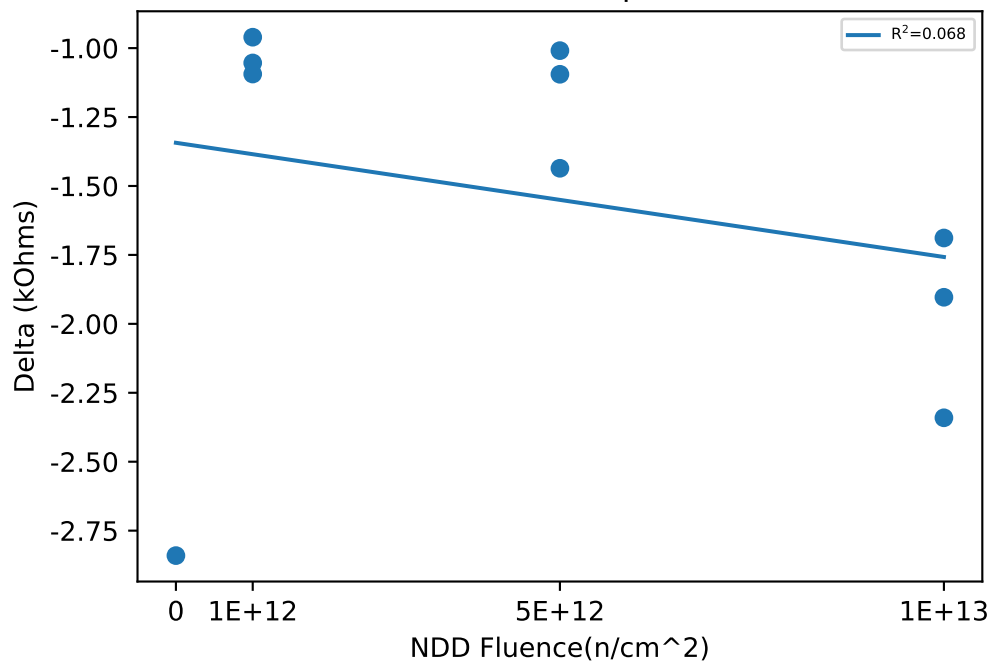
NDD vs Result Stats



Test Results (Lower Limit = 100.0, Upper Limit = 400.0 (kOhms))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	195.49	194.53	-0.9604
551	1e+12	NDD	212.19	211.1	-1.094
552	1e+12	NDD	197.89	196.84	-1.0538
553	5e+12	NDD	199.39	197.96	-1.4358
554	5e+12	NDD	193.49	192.48	-1.0091
555	5e+12	NDD	207.99	206.89	-1.0949
556	1e+13	NDD	204.35	202.66	-1.6886
557	1e+13	NDD	197	195.09	-1.9036
558	1e+13	NDD	192.42	190.08	-2.3407
559	0	NDD, Ctrl	194.88	192.04	-2.8405

NDD vs Post - Pre Exposure Delta

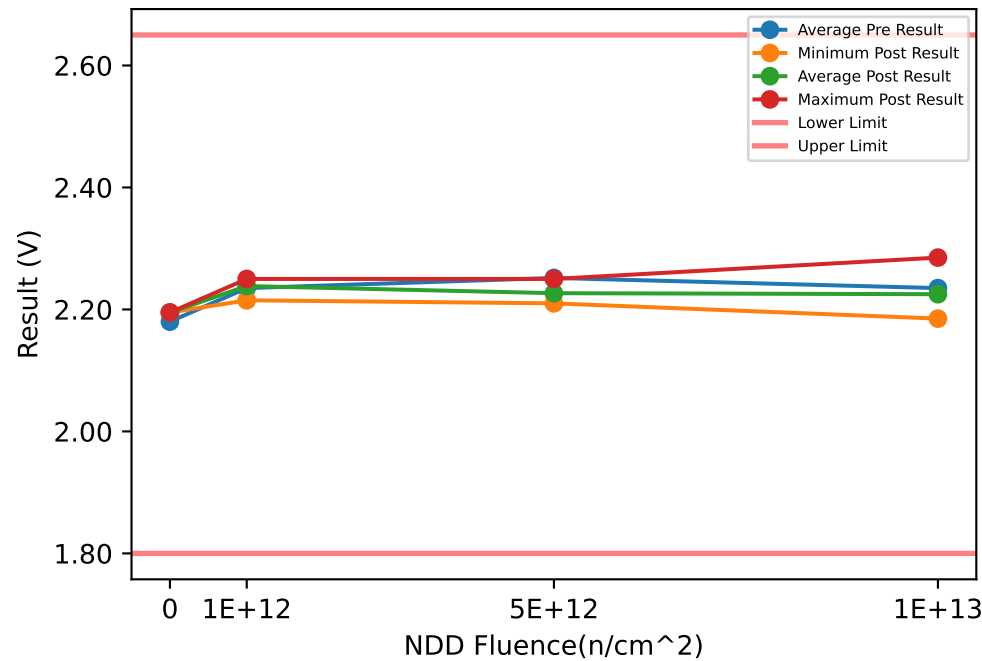


Test Statistics (kOhms)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	194.88	194.88	194.88		192.04	192.04	192.04		-2.8405	-2.8405	-2.8405	
1e+12	195.49	201.86	212.19	9.0288	194.53	200.82	211.1	8.973	-1.094	-1.0361	-0.9604	0.068543
5e+12	193.49	200.29	207.99	7.2926	192.48	199.11	206.89	7.277	-1.4358	-1.1799	-1.0091	0.2257
1e+13	192.42	197.92	204.35	6.0184	190.08	195.94	202.66	6.334	-2.3407	-1.9776	-1.6886	0.33229

Device Test: 92.0 V_PWM_LI_IH(PWM_LI Rise Thresh VIN_14V)

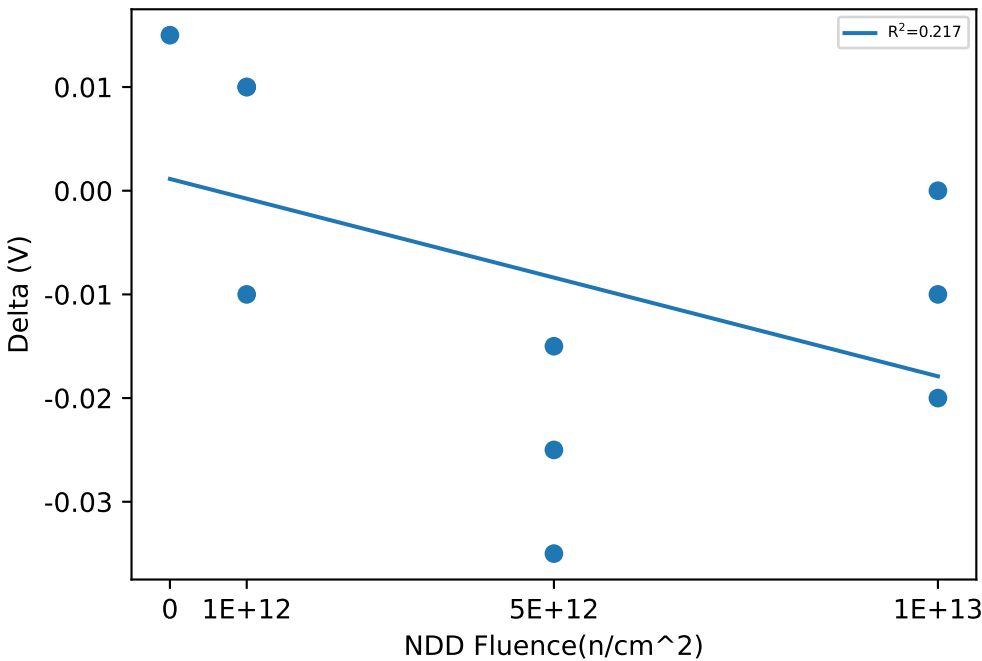
NDD vs Result Stats



Test Results (Lower Limit = 1.8, Upper Limit = 2.65 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	2.225	2.215	-0.01
551	1e+12	NDD	2.24	2.25	0.01
552	1e+12	NDD	2.24	2.25	0.01
553	5e+12	NDD	2.275	2.25	-0.025
554	5e+12	NDD	2.235	2.22	-0.015
555	5e+12	NDD	2.245	2.21	-0.035
556	1e+13	NDD	2.215	2.205	-0.01
557	1e+13	NDD	2.205	2.185	-0.02
558	1e+13	NDD	2.285	2.285	0
559	0	NDD, Ctrl	2.18	2.195	0.015

NDD vs Post - Pre Exposure Delta

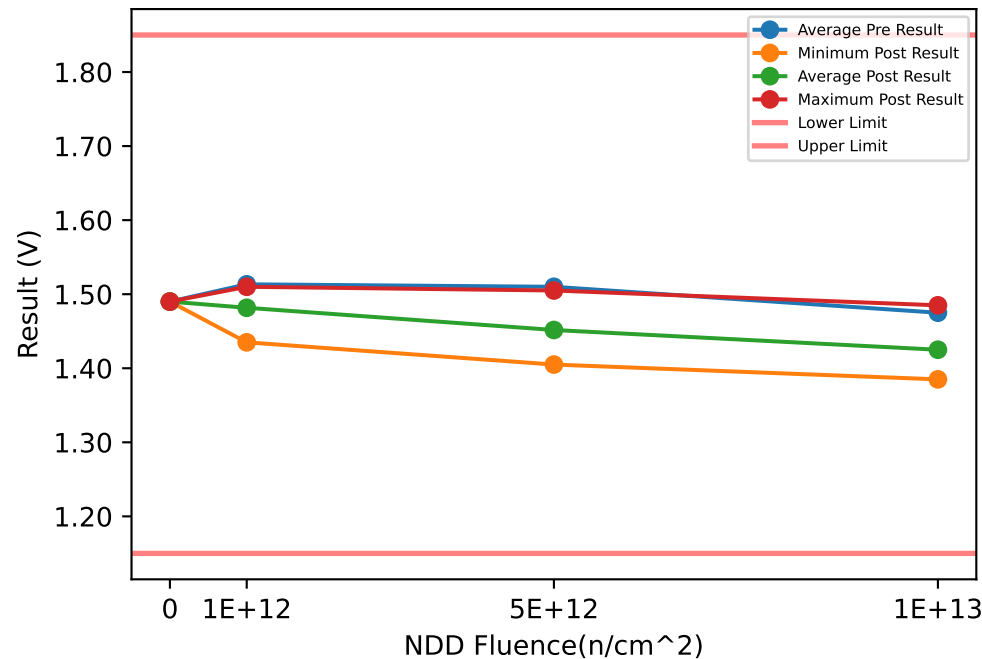


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.18	2.18	2.18		2.195	2.195	2.195		0.015	0.015	0.015	
1e+12	2.225	2.235	2.24	0.0086603	2.215	2.2383	2.25	0.020207	-0.01	0.0033333	0.01	0.011547
5e+12	2.235	2.2517	2.275	0.020817	2.21	2.2267	2.25	0.020817	-0.035	-0.025	-0.015	0.01
1e+13	2.205	2.235	2.285	0.043589	2.185	2.225	2.285	0.052915	-0.02	-0.01	0	0.01

Device Test: 92.1 V_PWM_LI_IL(PWM_LI Fall Thresh VIN_14V)

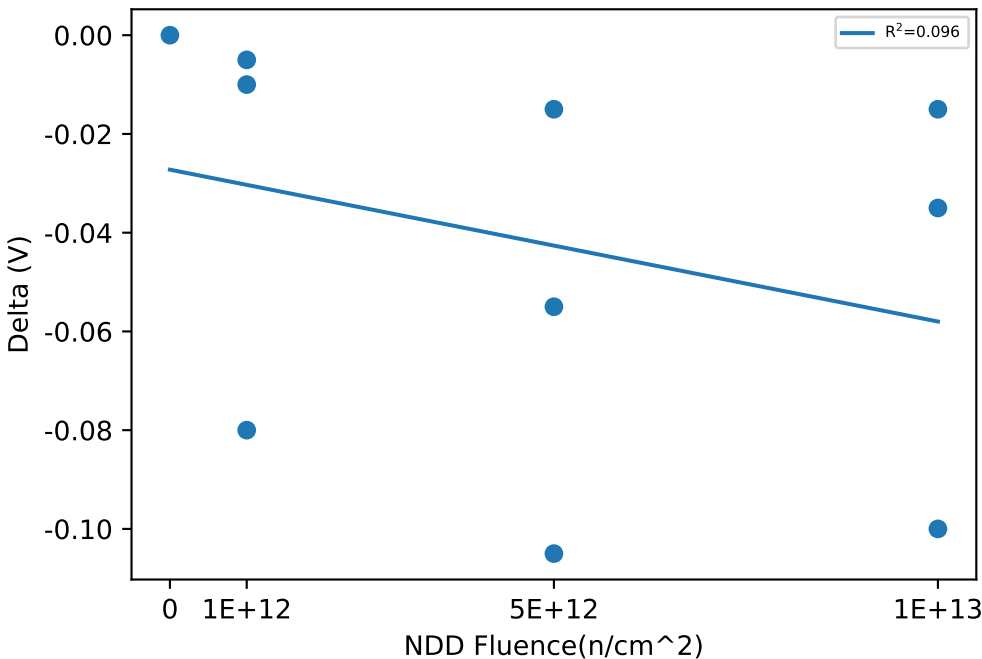
NDD vs Result Stats



Test Results (Lower Limit = 1.15, Upper Limit = 1.85 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	1.51	1.5	-0.01
551	1e+12	NDD	1.515	1.435	-0.08
552	1e+12	NDD	1.515	1.51	-0.005
553	5e+12	NDD	1.51	1.405	-0.105
554	5e+12	NDD	1.5	1.445	-0.055
555	5e+12	NDD	1.52	1.505	-0.015
556	1e+13	NDD	1.5	1.485	-0.015
557	1e+13	NDD	1.505	1.405	-0.1
558	1e+13	NDD	1.42	1.385	-0.035
559	0	NDD, Ctrl	1.49	1.49	0

NDD vs Post - Pre Exposure Delta

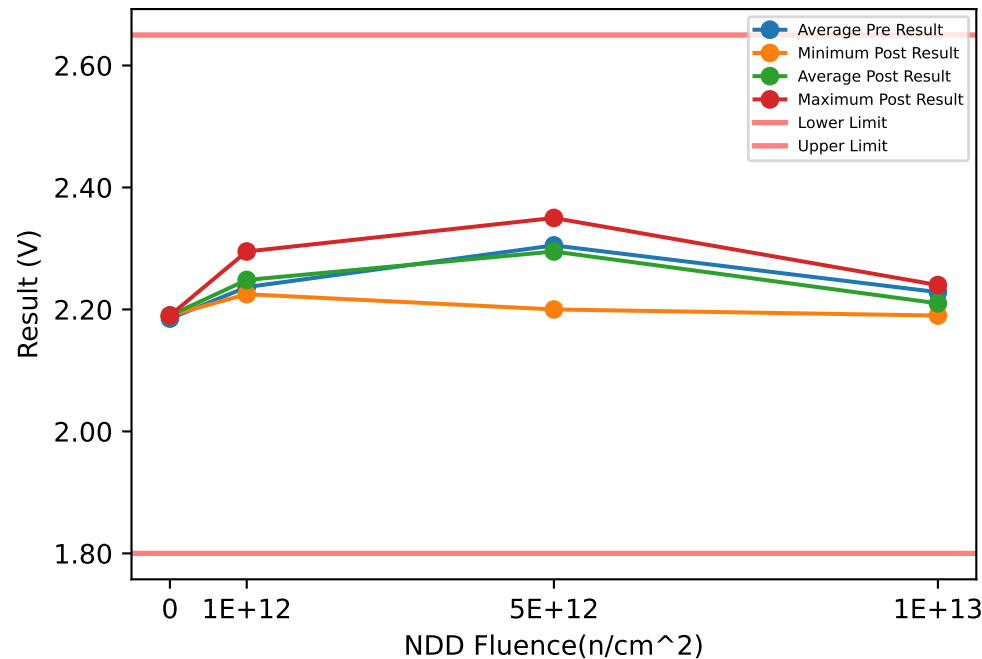


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.49	1.49	1.49		1.49	1.49	1.49		0	0	0	
1e+12	1.51	1.5133	1.515	0.0028868	1.435	1.4817	1.51	0.040723	-0.08	-0.031667	-0.005	0.041932
5e+12	1.5	1.51	1.52	0.01	1.405	1.4517	1.505	0.050332	-0.105	-0.058333	-0.015	0.045092
1e+13	1.42	1.475	1.505	0.047697	1.385	1.425	1.485	0.052915	-0.1	-0.05	-0.015	0.044441

Device Test: 92.3 V_EN_HI_IH(EN_HI Rise Thresh VIN_14V)

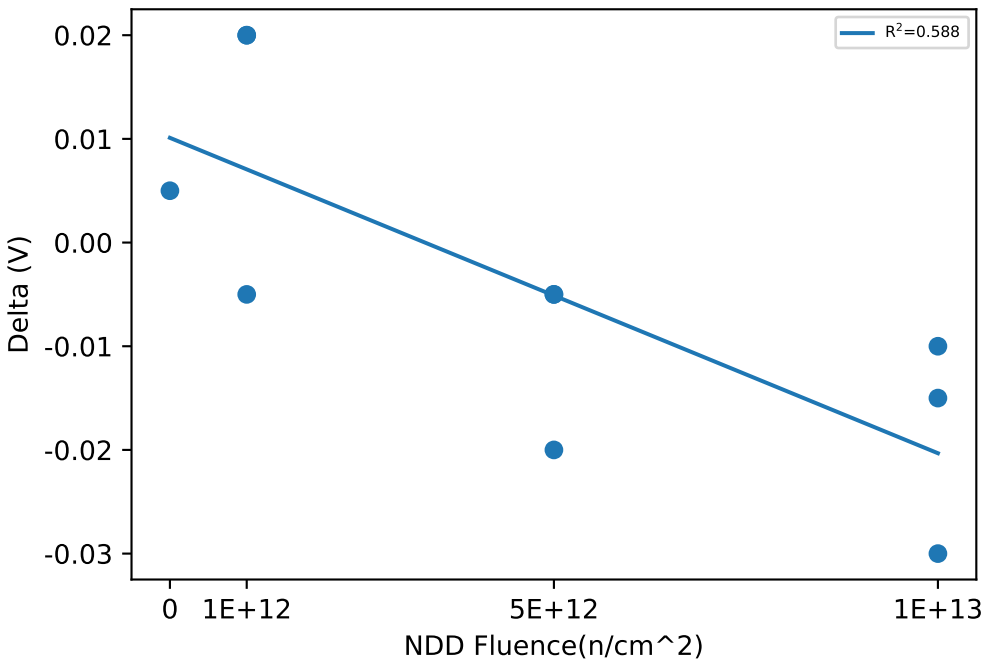
NDD vs Result Stats



Test Results (Lower Limit = 1.8, Upper Limit = 2.65 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	2.3	2.295	-0.005
551	1e+12	NDD	2.205	2.225	0.02
552	1e+12	NDD	2.205	2.225	0.02
553	5e+12	NDD	2.34	2.335	-0.005
554	5e+12	NDD	2.37	2.35	-0.02
555	5e+12	NDD	2.205	2.2	-0.005
556	1e+13	NDD	2.25	2.24	-0.01
557	1e+13	NDD	2.205	2.19	-0.015
558	1e+13	NDD	2.23	2.2	-0.03
559	0	NDD, Ctrl	2.185	2.19	0.005

NDD vs Post - Pre Exposure Delta

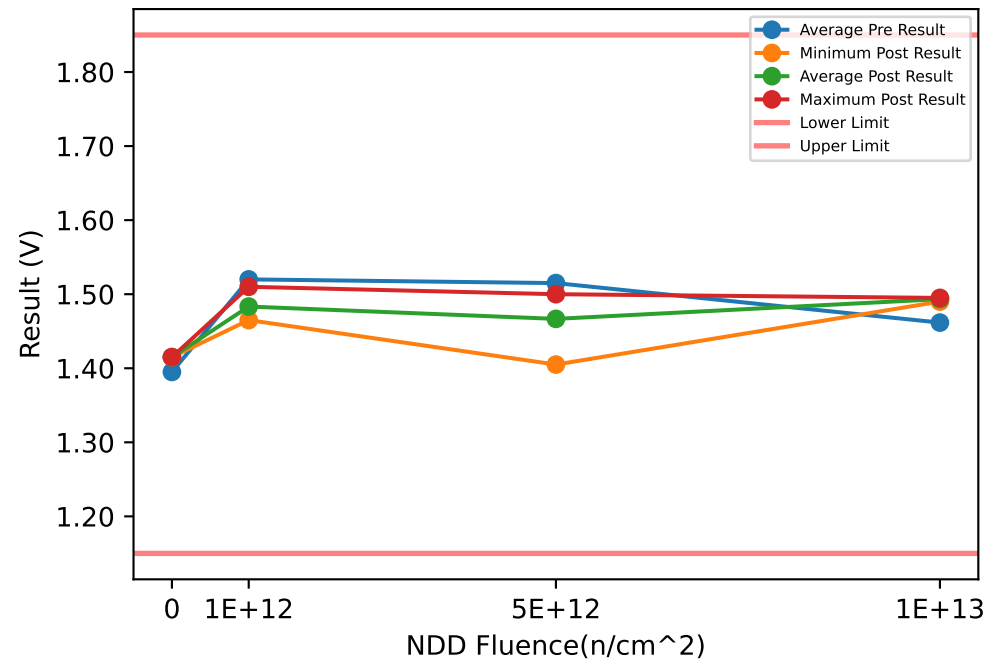


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.185	2.185	2.185		2.19	2.19	2.19		0.005	0.005	0.005	
1e+12	2.205	2.2367	2.3	0.054848	2.225	2.2483	2.295	0.040415	-0.005	0.011667	0.02	0.014434
5e+12	2.205	2.305	2.37	0.087892	2.2	2.295	2.35	0.082614	-0.02	-0.01	-0.005	0.0086603
1e+13	2.205	2.2283	2.25	0.022546	2.19	2.21	2.24	0.026458	-0.03	-0.018333	-0.01	0.010408

Device Test: 92.4 V_EN_HI_IL(EN_HI Fall Thresh VIN_14V)

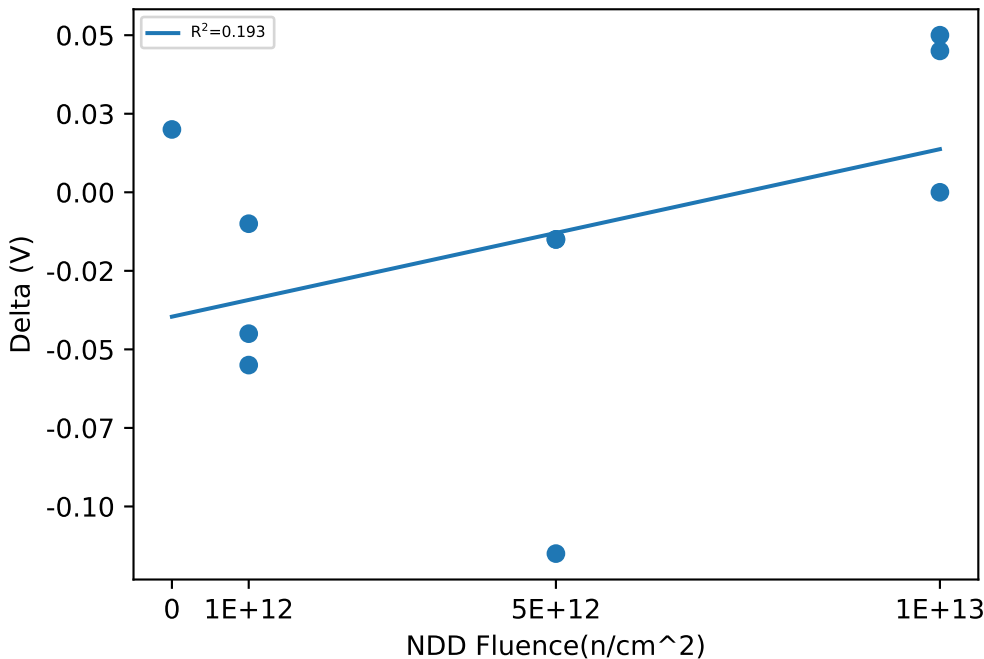
NDD vs Result Stats



Test Results (Lower Limit = 1.15, Upper Limit = 1.85 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	1.52	1.51	-0.01
551	1e+12	NDD	1.52	1.475	-0.045
552	1e+12	NDD	1.52	1.465	-0.055
553	5e+12	NDD	1.52	1.405	-0.115
554	5e+12	NDD	1.51	1.495	-0.015
555	5e+12	NDD	1.515	1.5	-0.015
556	1e+13	NDD	1.445	1.49	0.045
557	1e+13	NDD	1.445	1.495	0.05
558	1e+13	NDD	1.495	1.495	0
559	0	NDD, Ctrl	1.395	1.415	0.02

NDD vs Post - Pre Exposure Delta

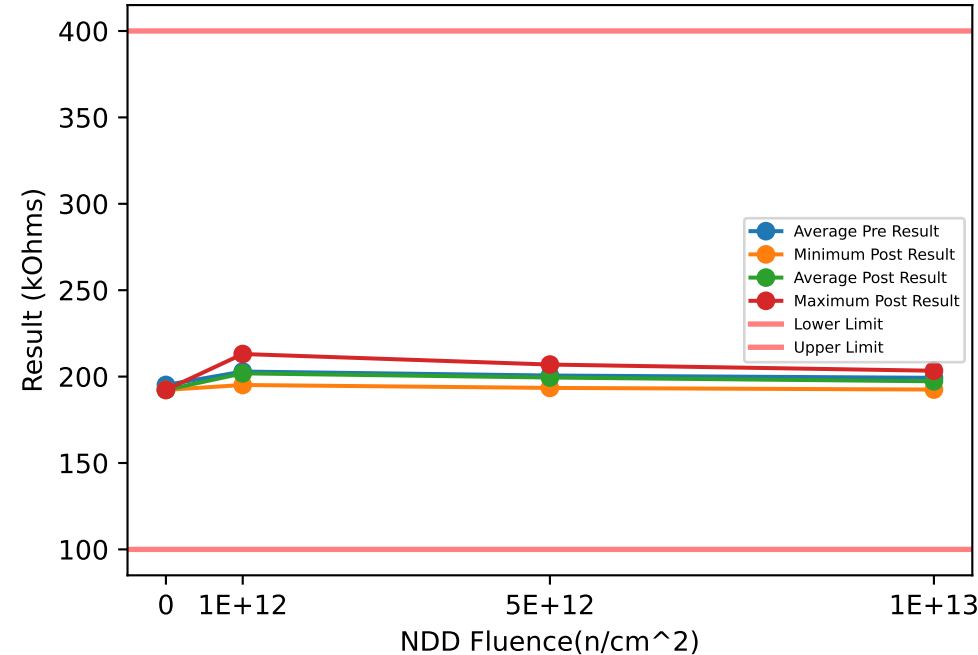


Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.395	1.395	1.395		1.415	1.415	1.415		0.02	0.02	0.02	
1e+12	1.52	1.52	1.52	0	1.465	1.4833	1.51	0.023629	-0.055	-0.036667	-0.01	0.023629
5e+12	1.51	1.515	1.52	0.005	1.405	1.4667	1.5	0.053463	-0.115	-0.048333	-0.015	0.057735
1e+13	1.445	1.4617	1.495	0.028868	1.49	1.4933	1.495	0.0028868	0	0.031667	0.05	0.027538

Device Test: 92.6 R_PWM_LI_PD(PWM_LI Pull Down Resistance VIN_14V)

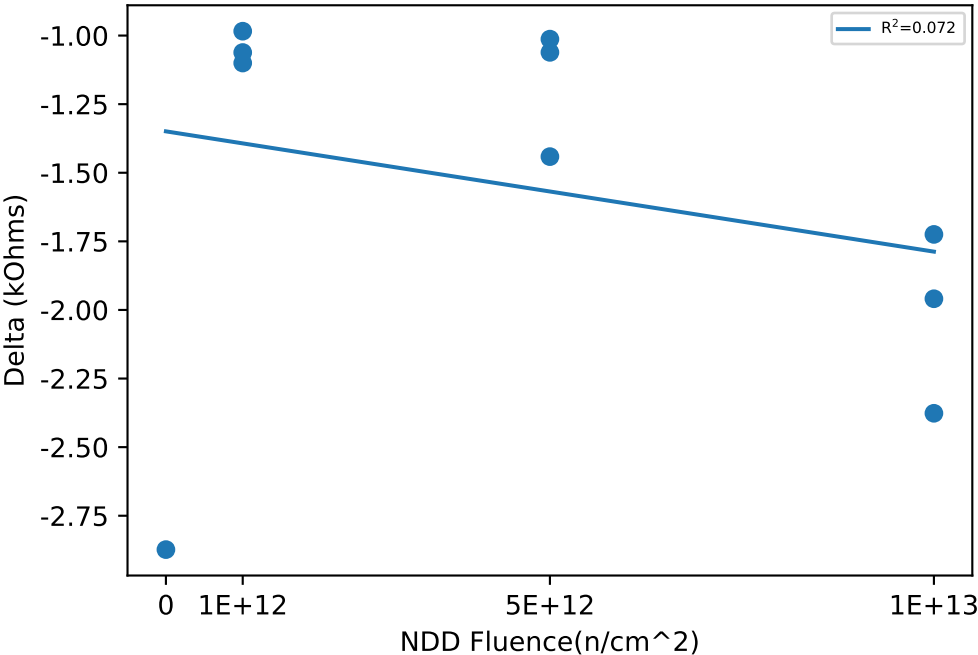
NDD vs Result Stats



Test Results (Lower Limit = 100.0, Upper Limit = 400.0 (kOhms))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	196.13	195.14	-0.9841
551	1e+12	NDD	214.18	213.08	-1.1001
552	1e+12	NDD	198.46	197.4	-1.0618
553	5e+12	NDD	199.38	197.94	-1.4412
554	5e+12	NDD	194.47	193.45	-1.013
555	5e+12	NDD	208.03	206.97	-1.0612
556	1e+13	NDD	205.11	203.39	-1.7247
557	1e+13	NDD	197.91	195.95	-1.9592
558	1e+13	NDD	194.87	192.49	-2.3766
559	0	NDD, Ctrl	195.17	192.3	-2.8734

NDD vs Post - Pre Exposure Delta

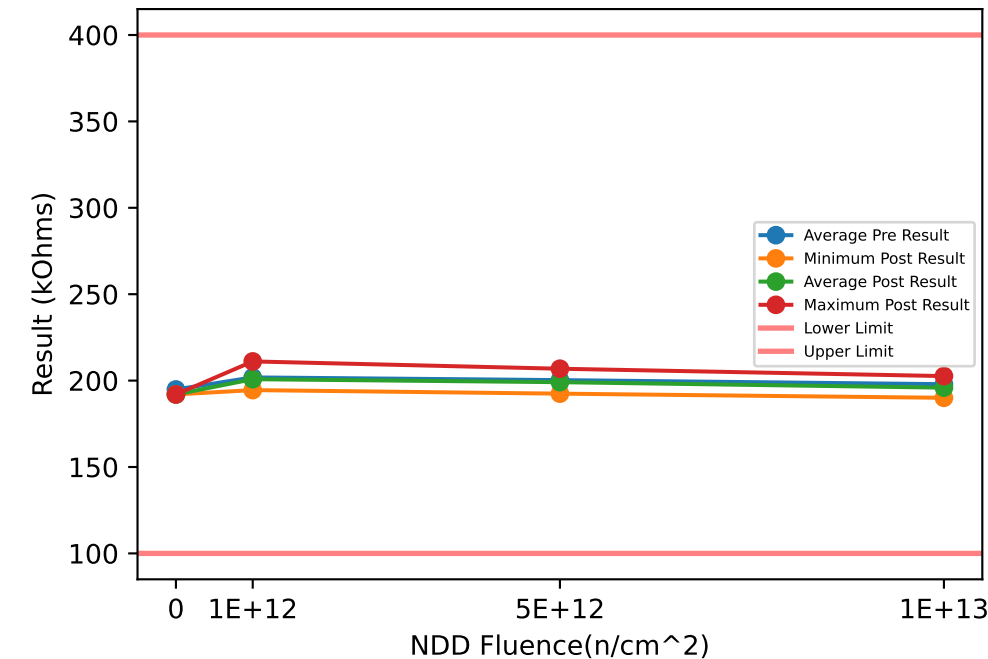


Test Statistics (kOhms)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	195.17	195.17	195.17		192.3	192.3	192.3		-2.8734	-2.8734	-2.8734	
1e+12	196.13	202.92	214.18	9.8167	195.14	201.87	213.08	9.7679	-1.1001	-1.0487	-0.9841	0.059105
5e+12	194.47	200.62	208.03	6.865	193.45	199.45	206.97	6.8818	-1.4412	-1.1718	-1.013	0.23455
1e+13	194.87	199.3	205.11	5.2609	192.49	197.28	203.39	5.5675	-2.3766	-2.0202	-1.7247	0.3302

Device Test: 92.7 R_EN_HI_PD(EN_HI Pull Down Resistance VIN_14V)

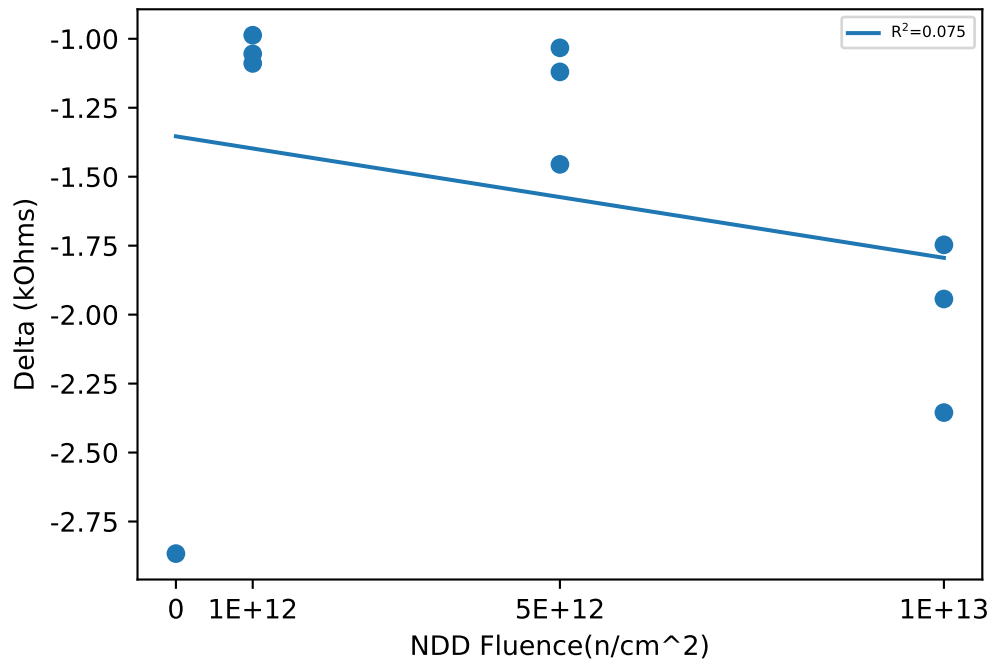
NDD vs Result Stats



Test Results (Lower Limit = 100.0, Upper Limit = 400.0 (kOhms))

Serial #	Fluence(n/cm ²)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	195.49	194.5	-0.987
551	1e+12	NDD	212.18	211.09	-1.0893
552	1e+12	NDD	197.88	196.82	-1.0547
553	5e+12	NDD	199.39	197.93	-1.4552
554	5e+12	NDD	193.47	192.44	-1.0328
555	5e+12	NDD	207.99	206.87	-1.12
556	1e+13	NDD	204.36	202.61	-1.747
557	1e+13	NDD	197.01	195.07	-1.9433
558	1e+13	NDD	192.4	190.05	-2.3551
559	0	NDD, Ctrl	194.86	192	-2.8663

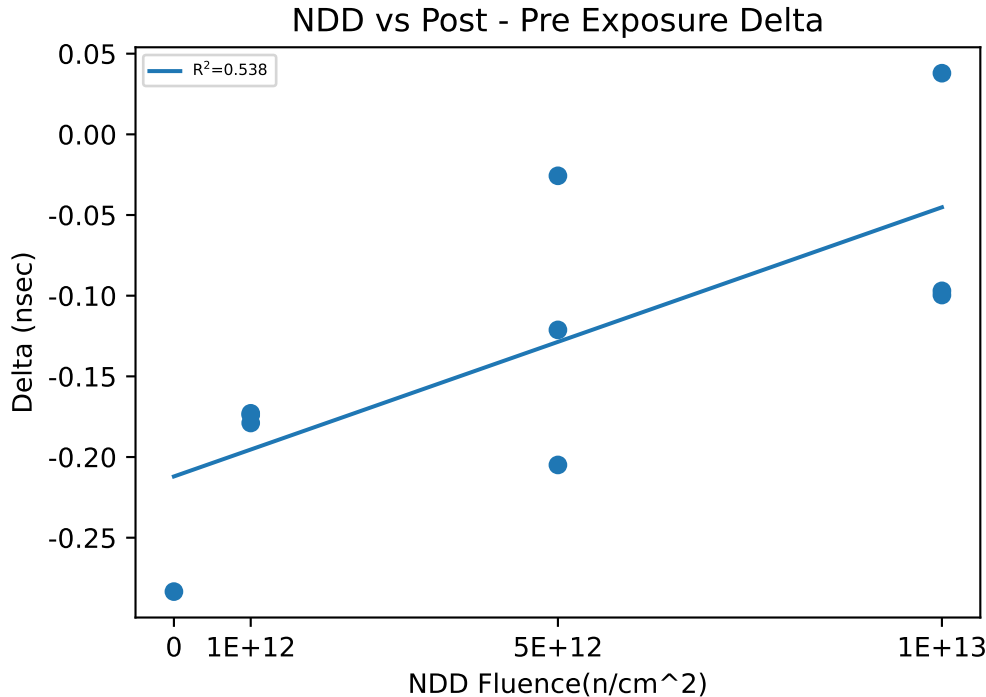
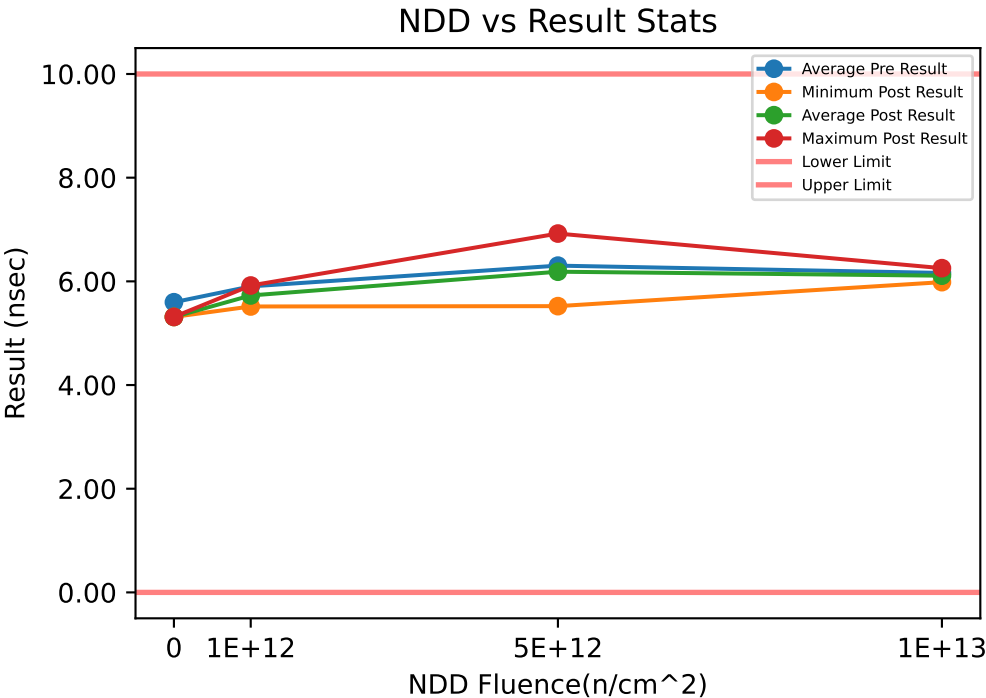
NDD vs Post - Pre Exposure Delta



Test Statistics (kOhms)

Fluence(n/cm ²)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	194.86	194.86	194.86		192	192	192		-2.8663	-2.8663	-2.8663	
1e+12	195.49	201.85	212.18	9.0293	194.5	200.81	211.09	8.9857	-1.0893	-1.0437	-0.987	0.052035
5e+12	193.47	200.28	207.99	7.299	192.44	199.08	206.87	7.2822	-1.4552	-1.2027	-1.0328	0.223
1e+13	192.4	197.92	204.36	6.0311	190.05	195.91	202.61	6.3251	-2.3551	-2.0151	-1.747	0.31035

Device Test: 95.0 T_RLH_MIN(DLH Dead Time Min 500kHz VIN_10V)



Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (nsec))

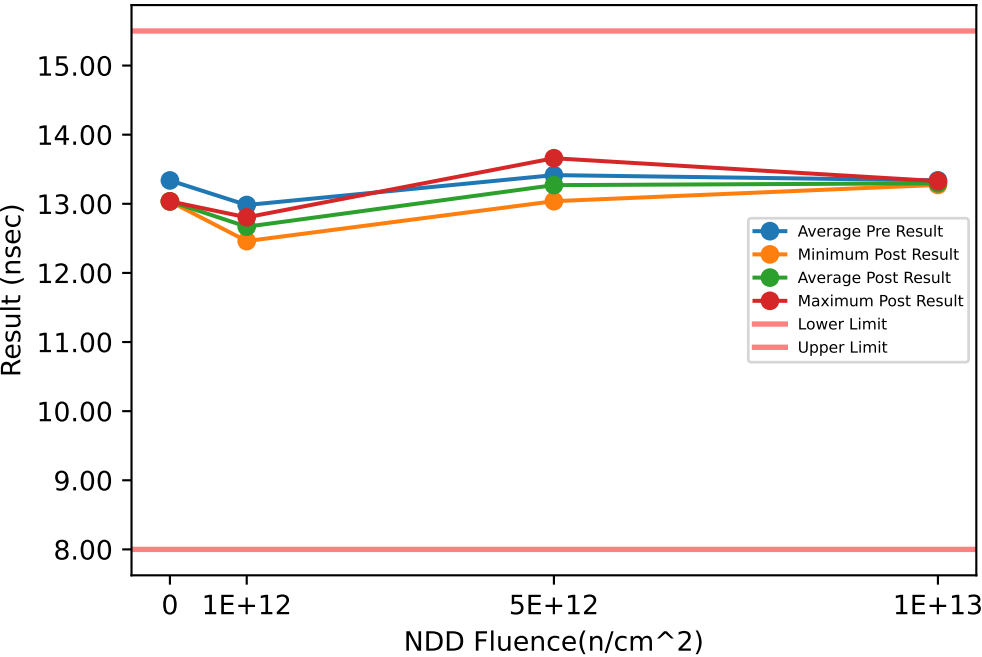
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	6.094	5.9201	-0.1739
551	1e+12	NDD	5.921	5.7481	-0.1729
552	1e+12	NDD	5.6944	5.5155	-0.1789
553	5e+12	NDD	6.3191	6.1142	-0.2049
554	5e+12	NDD	7.0432	6.922	-0.1212
555	5e+12	NDD	5.5475	5.5218	-0.0257
556	1e+13	NDD	6.3515	6.2545	-0.097
557	1e+13	NDD	6.0843	5.9847	-0.0996
558	1e+13	NDD	6.0513	6.0892	0.0379
559	0	NDD, Ctrl	5.5975	5.3141	-0.2834

Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.5975	5.5975	5.5975		5.3141	5.3141	5.3141		-0.2834	-0.2834	-0.2834	
1e+12	5.6944	5.9031	6.094	0.2004	5.5155	5.7279	5.9201	0.20305	-0.1789	-0.17523	-0.1729	0.0032146
5e+12	5.5475	6.3033	7.0432	0.74798	5.5218	6.186	6.922	0.70286	-0.2049	-0.11727	-0.0257	0.089665
1e+13	6.0513	6.1624	6.3515	0.16462	5.9847	6.1095	6.2545	0.13604	-0.0996	-0.0529	0.0379	0.078646

Device Test: 95.1 T_RLH_SMALL(DLH Dead Time Small 500kHz VIN_10V)

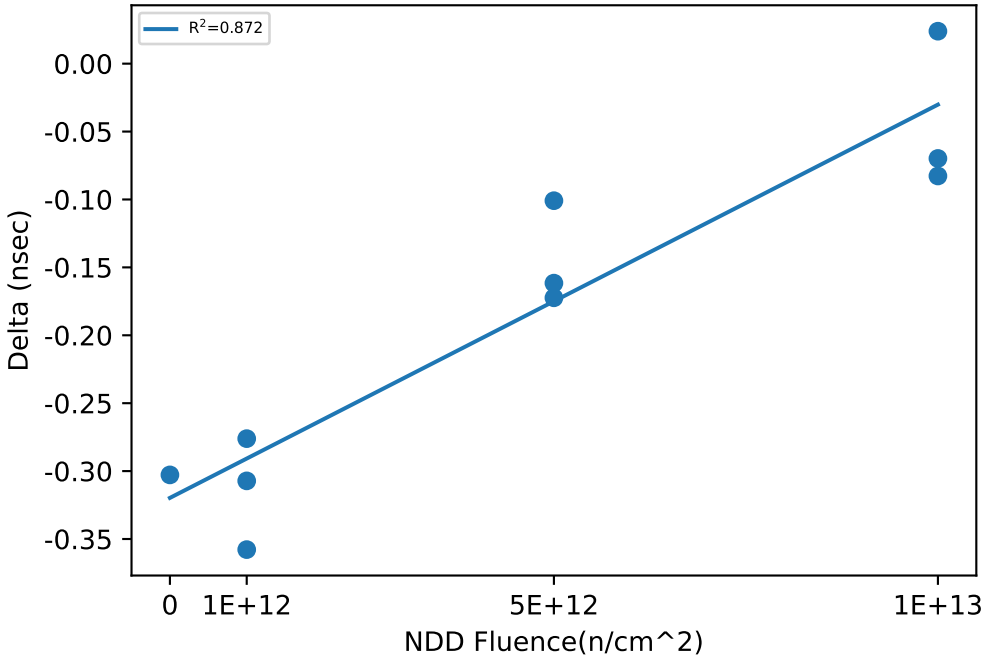
NDD vs Result Stats



Test Results (Lower Limit = 8.0, Upper Limit = 15.5 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	13.049	12.742	-0.3072
551	1e+12	NDD	12.818	12.46	-0.3578
552	1e+12	NDD	13.08	12.804	-0.2761
553	5e+12	NDD	13.275	13.113	-0.1616
554	5e+12	NDD	13.832	13.659	-0.1724
555	5e+12	NDD	13.139	13.038	-0.1009
556	1e+13	NDD	13.249	13.273	0.0239
557	1e+13	NDD	13.411	13.328	-0.0827
558	1e+13	NDD	13.358	13.289	-0.0698
559	0	NDD, Ctrl	13.338	13.035	-0.3028

NDD vs Post - Pre Exposure Delta

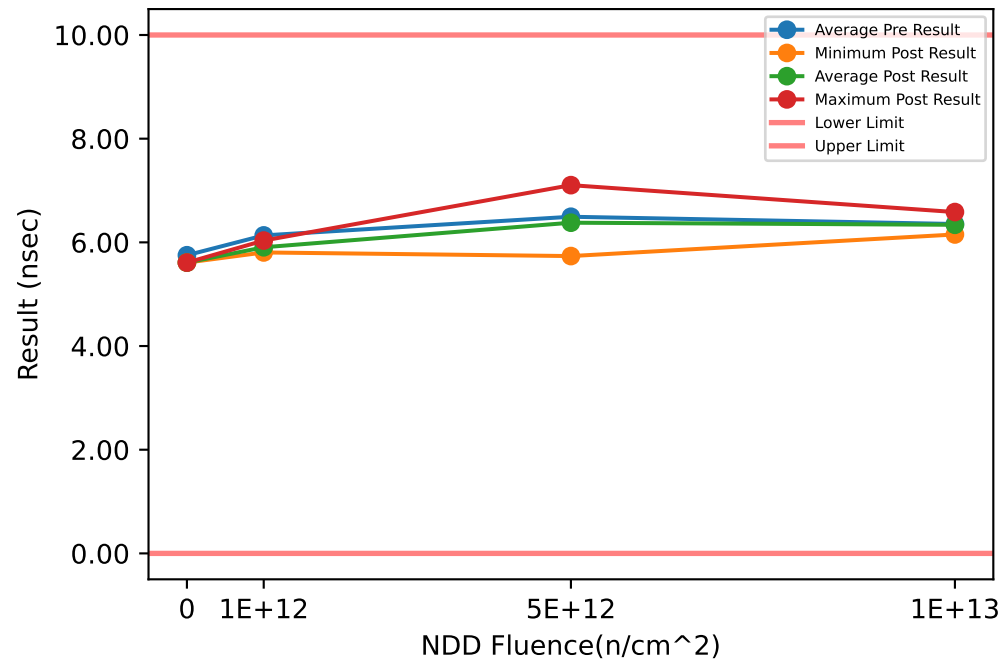


Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	13.338	13.338	13.338		13.035	13.035	13.035		-0.3028	-0.3028	-0.3028	
1e+12	12.818	12.982	13.08	0.14313	12.46	12.669	12.804	0.18315	-0.3578	-0.3137	-0.2761	0.041236
5e+12	13.139	13.415	13.832	0.36733	13.038	13.27	13.659	0.33931	-0.1724	-0.14497	-0.1009	0.038543
1e+13	13.249	13.339	13.411	0.082427	13.273	13.297	13.328	0.028276	-0.0827	-0.042867	0.0239	0.05818

Device Test: 95.10 T_RLH_MIN(DLH Dead Time Min 2MHz VIN_10V)

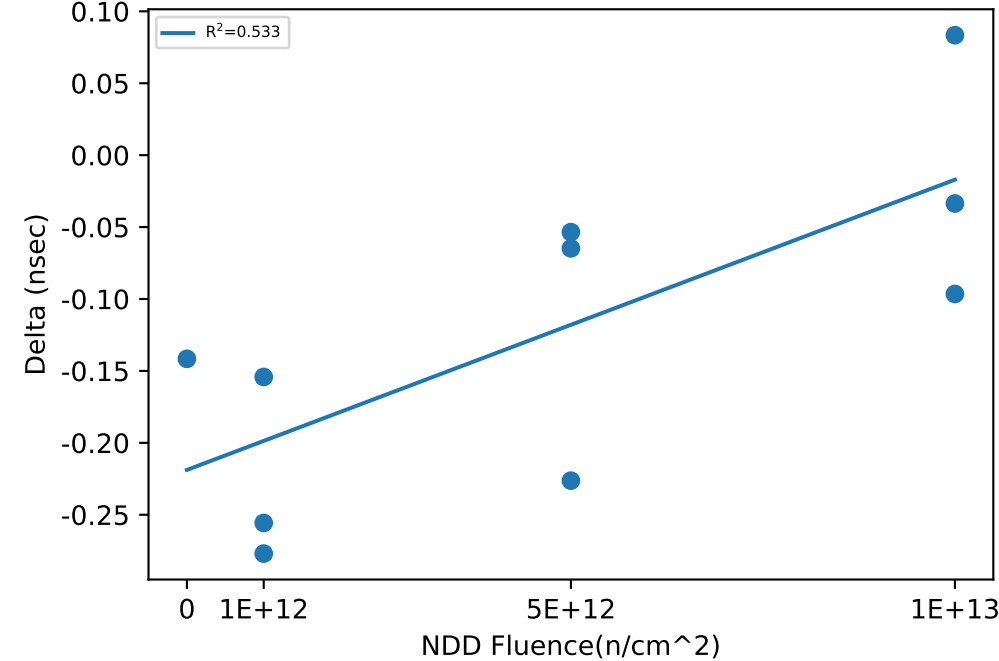
NDD vs Result Stats



Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	6.3118	6.0348	-0.277
551	1e+12	NDD	6.1309	5.8752	-0.2557
552	1e+12	NDD	5.9596	5.8054	-0.1542
553	5e+12	NDD	6.5245	6.2982	-0.2263
554	5e+12	NDD	7.1571	7.1036	-0.0535
555	5e+12	NDD	5.8003	5.7355	-0.0648
556	1e+13	NDD	6.5012	6.5846	0.0834
557	1e+13	NDD	6.2486	6.1521	-0.0965
558	1e+13	NDD	6.3134	6.2798	-0.0336
559	0	NDD, Ctrl	5.7515	5.6099	-0.1416

NDD vs Post - Pre Exposure Delta

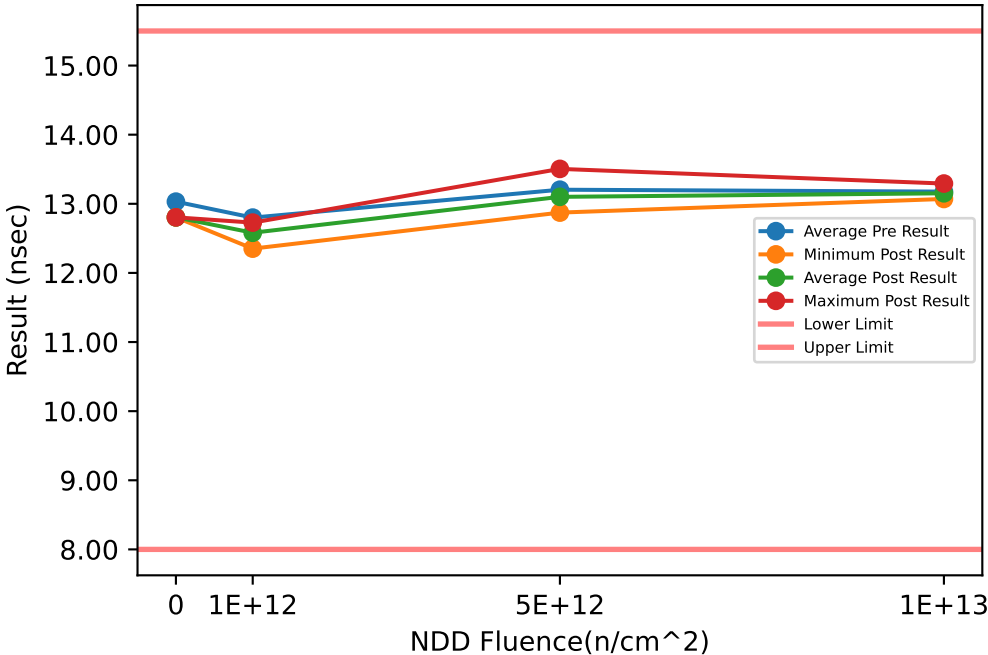


Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.7515	5.7515	5.7515		5.6099	5.6099	5.6099		-0.1416	-0.1416	-0.1416	
1e+12	5.9596	6.1341	6.3118	0.17612	5.8054	5.9051	6.0348	0.11759	-0.277	-0.22897	-0.1542	0.06562
5e+12	5.8003	6.494	7.1571	0.67892	5.7355	6.3791	7.1036	0.68763	-0.2263	-0.11487	-0.0535	0.096669
1e+13	6.2486	6.3544	6.5012	0.1312	6.1521	6.3388	6.5846	0.22221	-0.0965	-0.015567	0.0834	0.091296

Device Test: 95.11 T_RLH_SMALL(DLH Dead Time Small 2MHz VIN_10V)

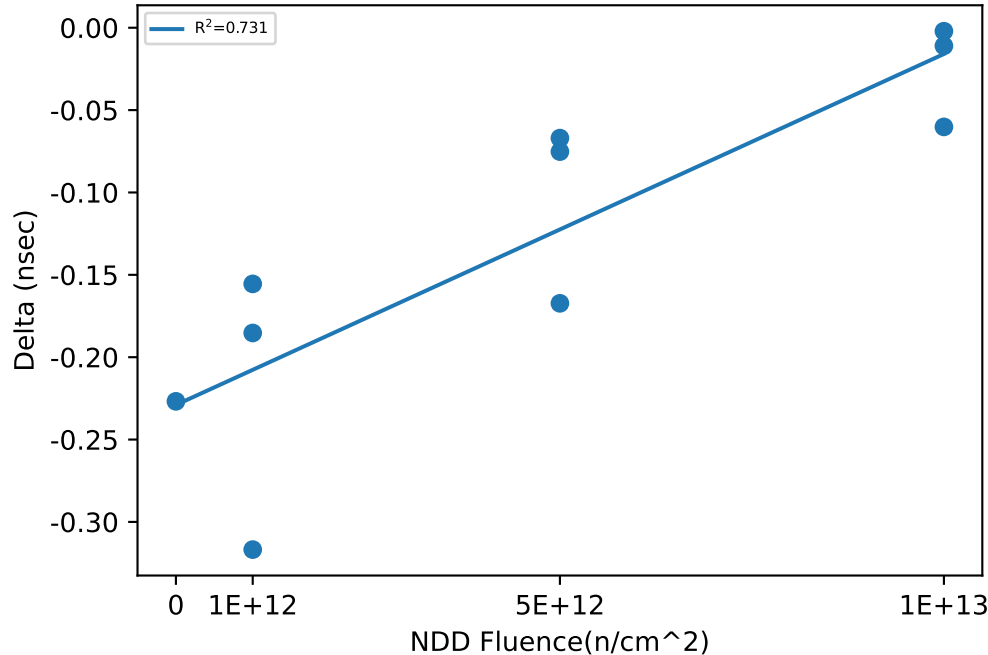
NDD vs Result Stats



Test Results (Lower Limit = 8.0, Upper Limit = 15.5 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	12.82	12.664	-0.1555
551	1e+12	NDD	12.668	12.351	-0.3168
552	1e+12	NDD	12.913	12.728	-0.1853
553	5e+12	NDD	12.999	12.924	-0.0752
554	5e+12	NDD	13.672	13.505	-0.1673
555	5e+12	NDD	12.94	12.873	-0.067
556	1e+13	NDD	13.13	13.07	-0.0602
557	1e+13	NDD	13.304	13.293	-0.011
558	1e+13	NDD	13.095	13.093	-0.0021
559	0	NDD, Ctrl	13.031	12.804	-0.2268

NDD vs Post - Pre Exposure Delta

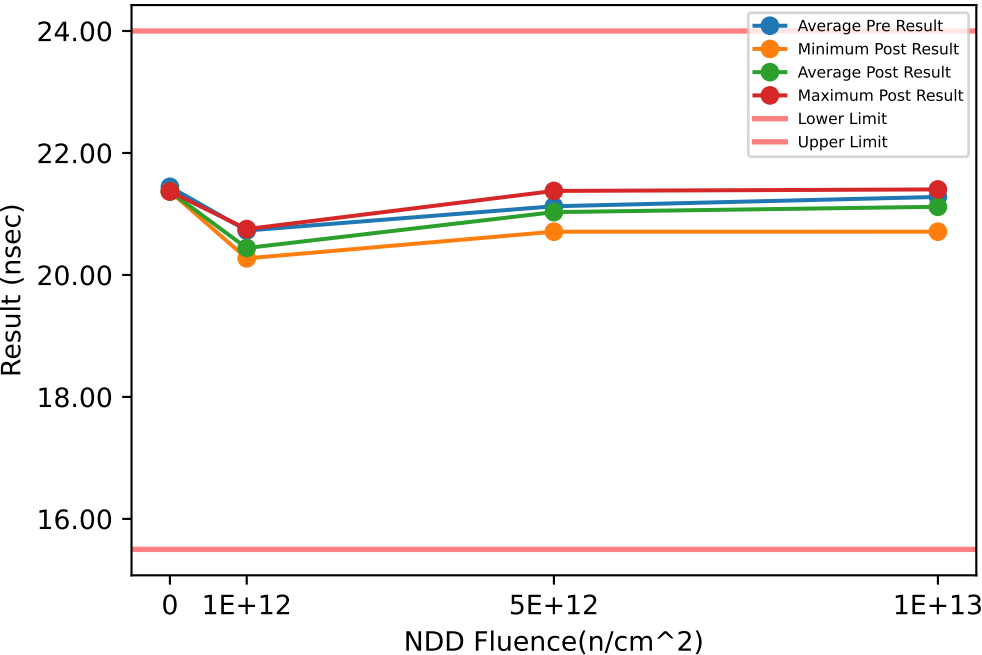


Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	13.031	13.031	13.031		12.804	12.804	12.804		-0.2268	-0.2268	-0.2268	
1e+12	12.668	12.8	12.913	0.12362	12.351	12.581	12.728	0.20154	-0.3168	-0.2192	-0.1555	0.085827
5e+12	12.94	13.204	13.672	0.4068	12.873	13.101	13.505	0.35111	-0.1673	-0.10317	-0.067	0.055692
1e+13	13.095	13.176	13.304	0.11192	13.07	13.152	13.293	0.12271	-0.0602	-0.024433	-0.0021	0.031293

Device Test: 95.12 T_RLH_MID(DLH Dead Time Mid 2MHz VIN_10V)

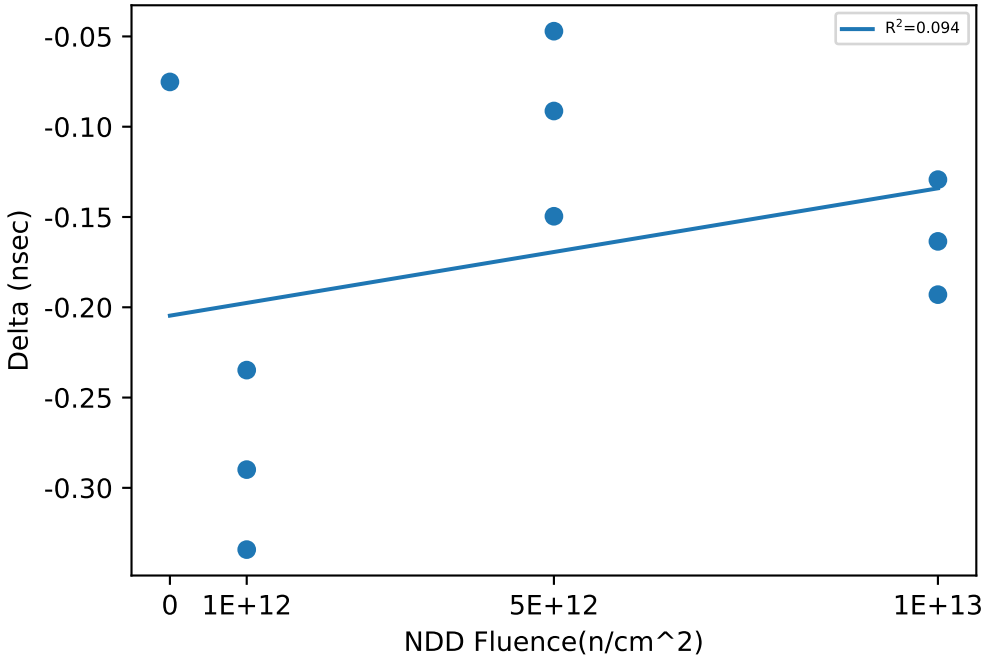
NDD vs Result Stats



Test Results (Lower Limit = 15.5, Upper Limit = 24.0 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	20.636	20.302	-0.3342
551	1e+12	NDD	20.507	20.272	-0.2348
552	1e+12	NDD	21.042	20.752	-0.2899
553	5e+12	NDD	20.859	20.709	-0.1496
554	5e+12	NDD	21.094	21.003	-0.0913
555	5e+12	NDD	21.425	21.378	-0.0471
556	1e+13	NDD	20.839	20.71	-0.1293
557	1e+13	NDD	21.595	21.402	-0.193
558	1e+13	NDD	21.404	21.241	-0.1635
559	0	NDD, Ctrl	21.445	21.369	-0.0752

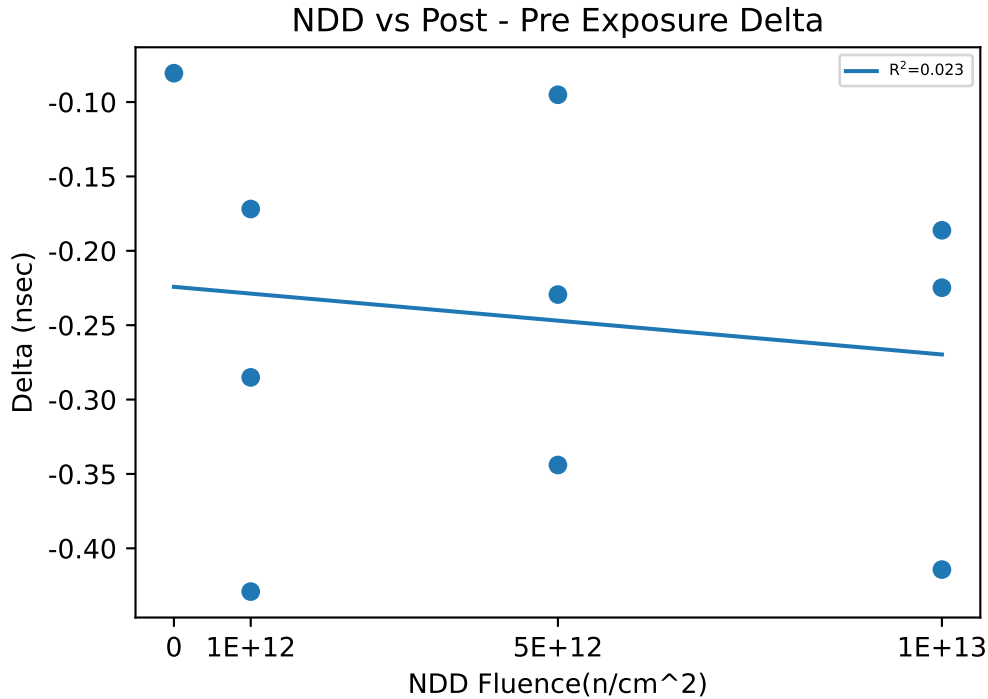
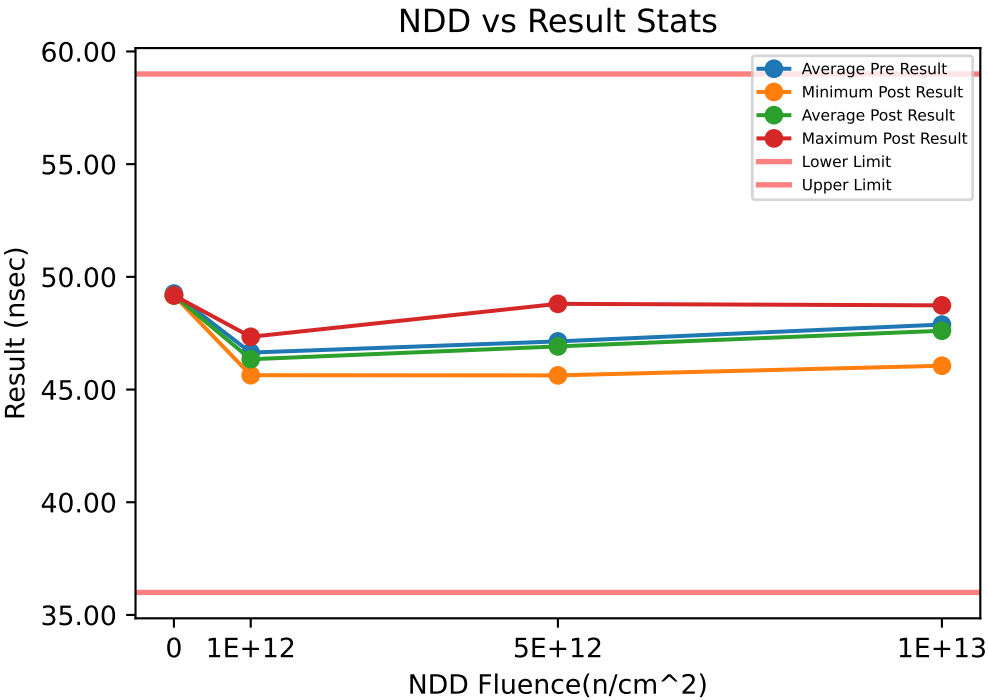
NDD vs Post - Pre Exposure Delta



Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	21.445	21.445	21.445		21.369	21.369	21.369		-0.0752	-0.0752	-0.0752	
1e+12	20.507	20.728	21.042	0.27917	20.272	20.442	20.752	0.26886	-0.3342	-0.2863	-0.2348	0.049798
5e+12	20.859	21.126	21.425	0.28427	20.709	21.03	21.378	0.33501	-0.1496	-0.096	-0.0471	0.051411
1e+13	20.839	21.279	21.595	0.39325	20.71	21.118	21.402	0.36233	-0.193	-0.16193	-0.1293	0.031879

Device Test: 95.13 T_RLH_LARGE(DLH Dead Time Large 2MHz VIN_10V)



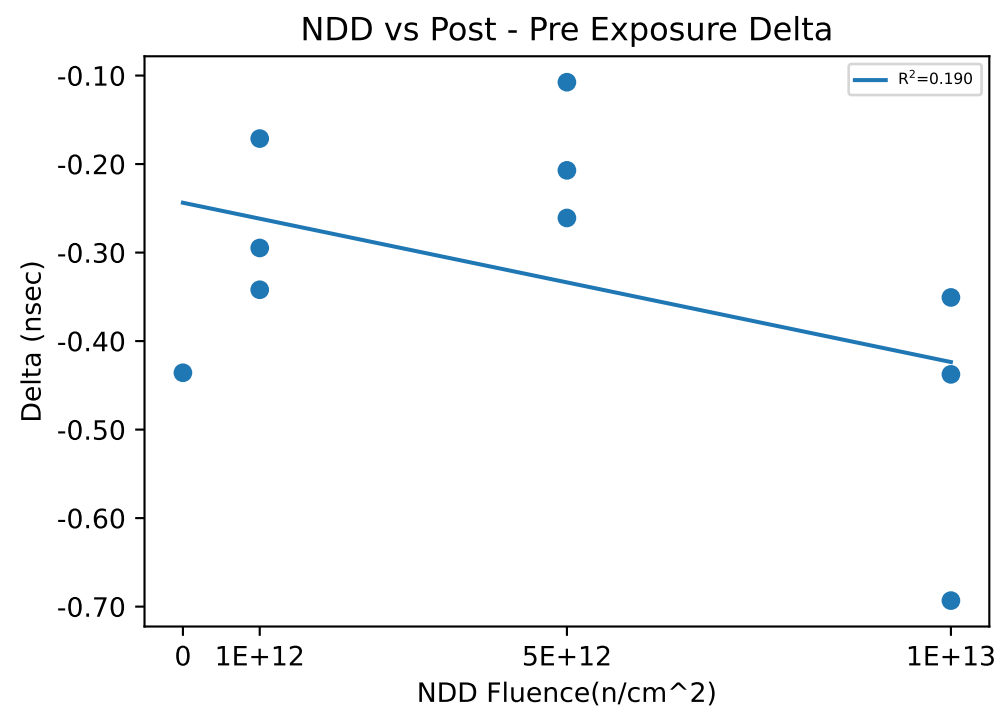
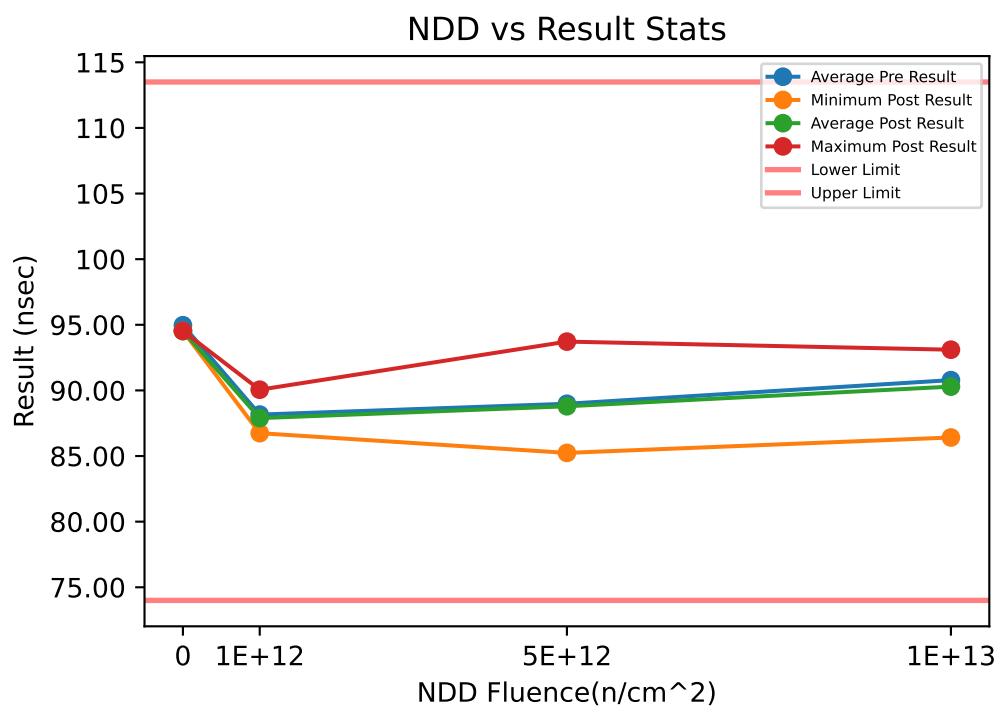
Test Results (Lower Limit = 36.0, Upper Limit = 59.0 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	46.228	46.056	-0.1719
551	1e+12	NDD	46.065	45.636	-0.4291
552	1e+12	NDD	47.626	47.34	-0.2851
553	5e+12	NDD	46.54	46.311	-0.2294
554	5e+12	NDD	45.973	45.629	-0.344
555	5e+12	NDD	48.897	48.802	-0.0951
556	1e+13	NDD	46.242	46.056	-0.1862
557	1e+13	NDD	48.96	48.735	-0.2248
558	1e+13	NDD	48.446	48.032	-0.4143
559	0	NDD, Ctrl	49.258	49.177	-0.0806

Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	49.258	49.258	49.258		49.177	49.177	49.177		-0.0806	-0.0806	-0.0806	
1e+12	46.065	46.64	47.626	0.85767	45.636	46.344	47.34	0.88789	-0.4291	-0.29537	-0.1719	0.12891
5e+12	45.973	47.137	48.897	1.5508	45.629	46.914	48.802	1.6704	-0.344	-0.22283	-0.0951	0.12458
1e+13	46.242	47.883	48.96	1.4438	46.056	47.608	48.735	1.389	-0.4143	-0.2751	-0.1862	0.12209

Device Test: 95.14 T_RLH_MAX(DLH Dead Time Max 2MHz VIN_10V)



Test Results (Lower Limit = 74.0, Upper Limit = 113.5 (nsec))

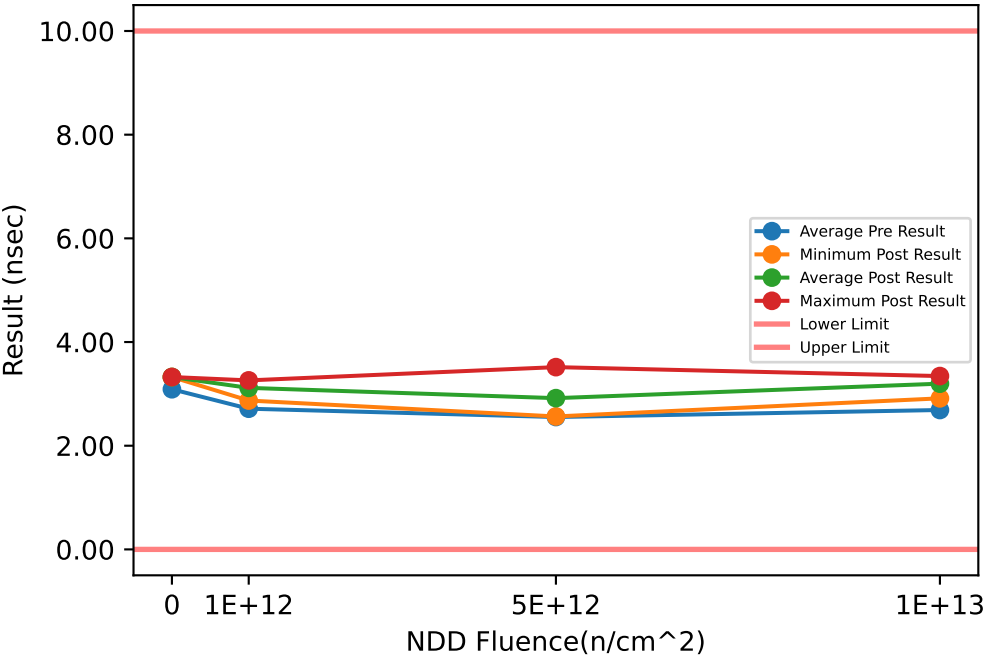
Serial #	Fluence(n/cm ²)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	87.038	86.743	-0.2948
551	1e+12	NDD	87.04	86.869	-0.1712
552	1e+12	NDD	90.396	90.054	-0.342
553	5e+12	NDD	87.621	87.414	-0.2071
554	5e+12	NDD	85.5	85.239	-0.2609
555	5e+12	NDD	93.826	93.718	-0.1075
556	1e+13	NDD	86.763	86.412	-0.3507
557	1e+13	NDD	93.54	93.102	-0.4376
558	1e+13	NDD	92.047	91.354	-0.6932
559	0	NDD, Ctrl	94.966	94.53	-0.4358

Test Statistics (nsec)

Fluence(n/cm ²)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	94.966	94.966	94.966		94.53	94.53	94.53		-0.4358	-0.4358	-0.4358	
1e+12	87.038	88.158	90.396	1.9378	86.743	87.889	90.054	1.8759	-0.342	-0.26933	-0.1712	0.088202
5e+12	85.5	88.982	93.826	4.3265	85.239	88.791	93.718	4.4039	-0.2609	-0.19183	-0.1075	0.077831
1e+13	86.763	90.783	93.54	3.5608	86.412	90.29	93.102	3.4696	-0.6932	-0.49383	-0.3507	0.17804

Device Test: 95.19 T_RHL_MIN(DHL Dead Time Min 500kHz VIN_10V)

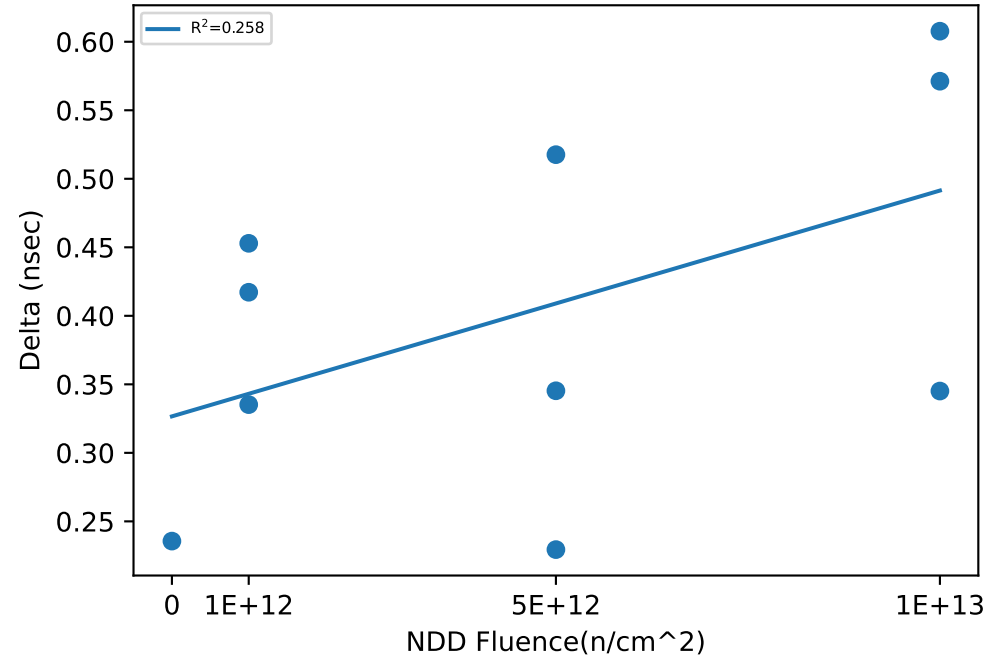
NDD vs Result Stats



Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	2.7987	3.2159	0.4172
551	1e+12	NDD	2.4186	2.8715	0.4529
552	1e+12	NDD	2.925	3.2602	0.3352
553	5e+12	NDD	2.9983	3.5159	0.5176
554	5e+12	NDD	2.2192	2.5645	0.3453
555	5e+12	NDD	2.443	2.6724	0.2294
556	1e+13	NDD	2.5688	2.9139	0.3451
557	1e+13	NDD	2.7254	3.3331	0.6077
558	1e+13	NDD	2.7724	3.3436	0.5712
559	0	NDD, Ctrl	3.0894	3.325	0.2356

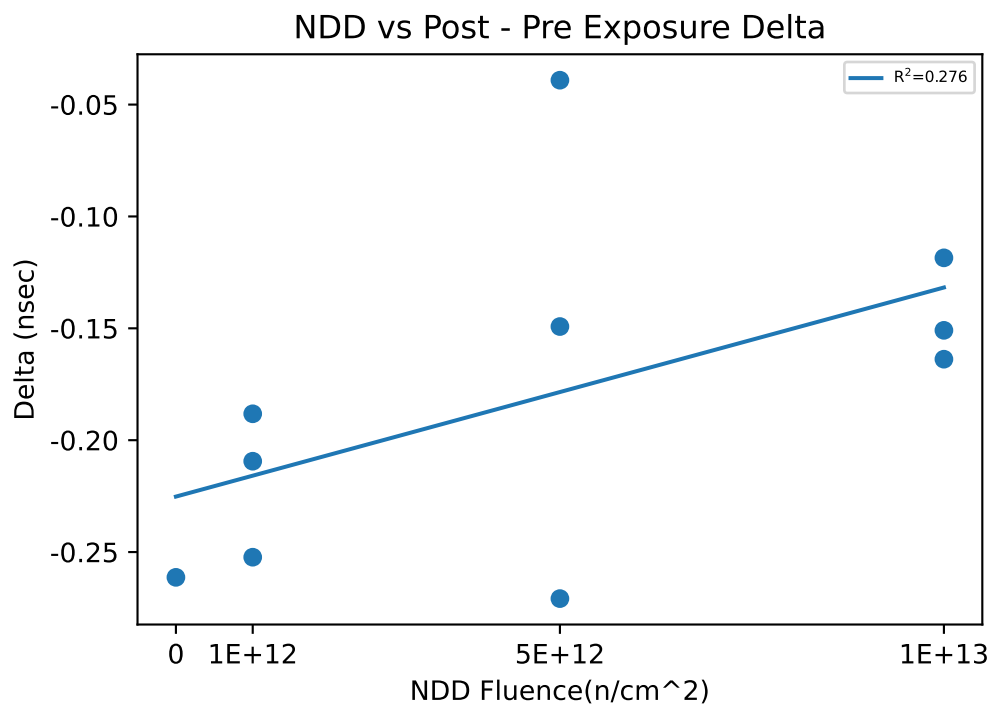
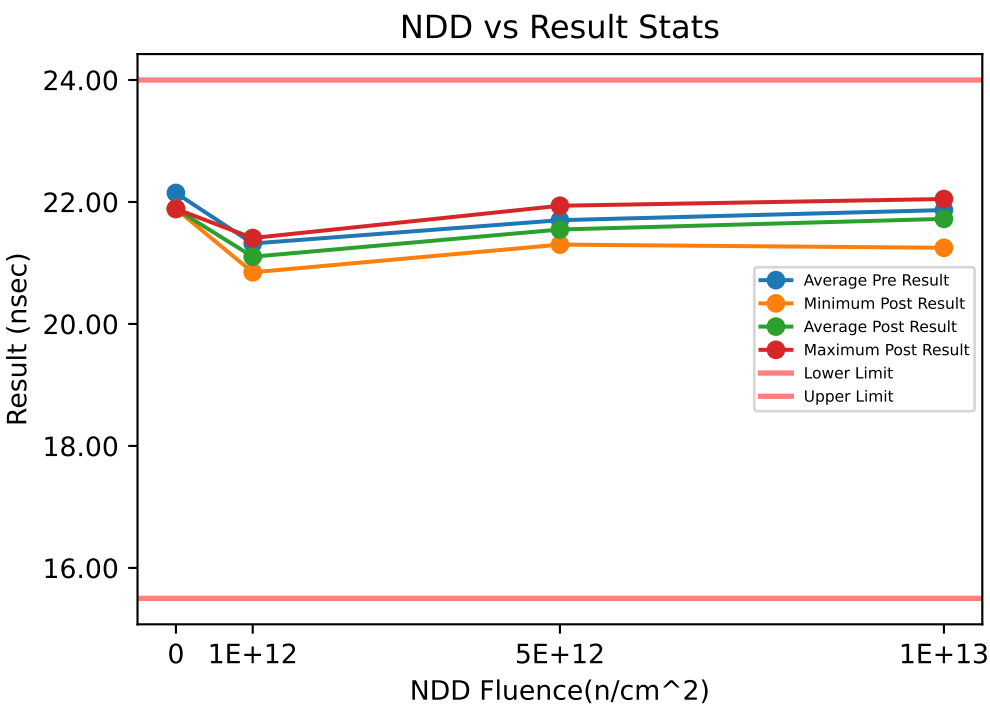
NDD vs Post - Pre Exposure Delta



Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.0894	3.0894	3.0894		3.325	3.325	3.325		0.2356	0.2356	0.2356	
1e+12	2.4186	2.7141	2.925	0.26359	2.8715	3.1159	3.2602	0.21278	0.3352	0.40177	0.4529	0.060349
5e+12	2.2192	2.5535	2.9983	0.40113	2.5645	2.9176	3.5159	0.52094	0.2294	0.3641	0.5176	0.14502
1e+13	2.5688	2.6889	2.7724	0.1066	2.9139	3.1969	3.3436	0.24511	0.3451	0.508	0.6077	0.14225

Device Test: 95.2 T_RLH_MID(DLH Dead Time Mid 500kHz VIN_10V)



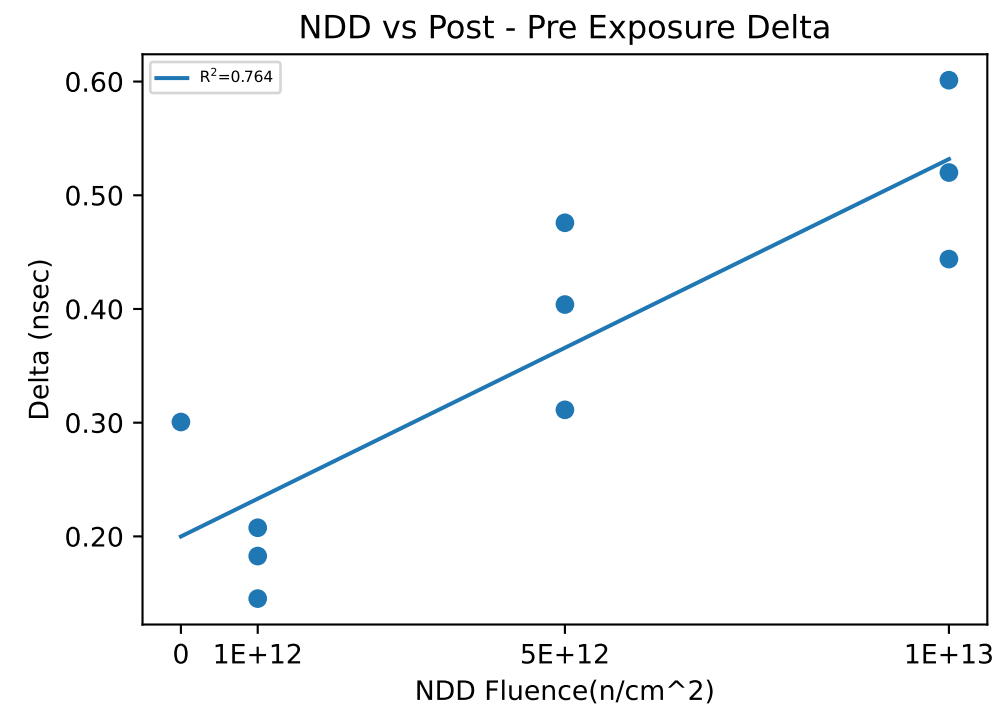
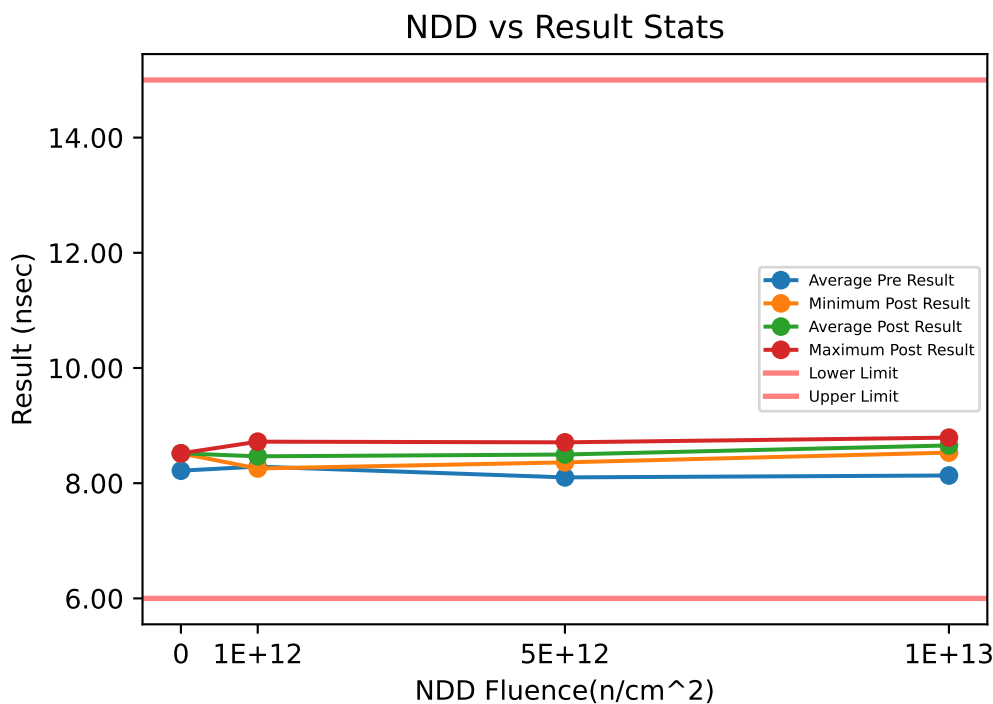
Test Results (Lower Limit = 15.5, Upper Limit = 24.0 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	21.24	21.052	-0.1882
551	1e+12	NDD	21.099	20.847	-0.2523
552	1e+12	NDD	21.619	21.409	-0.2094
553	5e+12	NDD	21.45	21.301	-0.1492
554	5e+12	NDD	21.677	21.406	-0.2708
555	5e+12	NDD	21.977	21.938	-0.0391
556	1e+13	NDD	21.367	21.249	-0.1185
557	1e+13	NDD	22.2	22.049	-0.1509
558	1e+13	NDD	22.035	21.871	-0.1638
559	0	NDD, Ctrl	22.148	21.887	-0.2613

Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	22.148	22.148	22.148		21.887	21.887	21.887		-0.2613	-0.2613	-0.2613	
1e+12	21.099	21.319	21.619	0.26863	20.847	21.103	21.409	0.2846	-0.2523	-0.21663	-0.1882	0.032656
5e+12	21.45	21.701	21.977	0.26451	21.301	21.548	21.938	0.34173	-0.2708	-0.15303	-0.0391	0.1159
1e+13	21.367	21.867	22.2	0.44061	21.249	21.723	22.049	0.41992	-0.1638	-0.1444	-0.1185	0.023339

Device Test: 95.20 T_RHL_SMALL(DHL Dead Time Small 500kHz VIN_10V)



Test Results (Lower Limit = 6.0, Upper Limit = 15.0 (nsec))

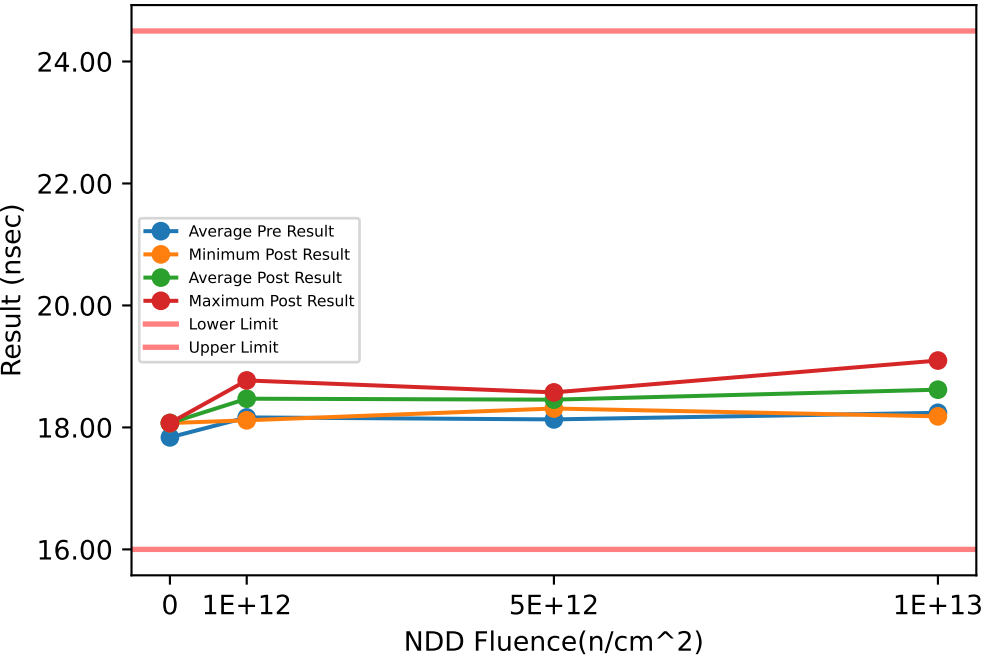
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	8.2409	8.4236	0.1827
551	1e+12	NDD	8.11	8.2553	0.1453
552	1e+12	NDD	8.5134	8.721	0.2076
553	5e+12	NDD	8.3982	8.7095	0.3113
554	5e+12	NDD	7.9577	8.3616	0.4039
555	5e+12	NDD	7.9464	8.4222	0.4758
556	1e+13	NDD	8.0874	8.5313	0.4439
557	1e+13	NDD	8.2709	8.7909	0.52
558	1e+13	NDD	8.043	8.6442	0.6012
559	0	NDD, Ctrl	8.2172	8.5178	0.3006

Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.2172	8.2172	8.2172		8.5178	8.5178	8.5178		0.3006	0.3006	0.3006	
1e+12	8.11	8.2881	8.5134	0.2058	8.2553	8.4666	8.721	0.23581	0.1453	0.17853	0.2076	0.031358
5e+12	7.9464	8.1008	8.3982	0.25765	8.3616	8.4978	8.7095	0.18585	0.3113	0.397	0.4758	0.082467
1e+13	8.043	8.1338	8.2709	0.12082	8.5313	8.6555	8.7909	0.13017	0.4439	0.5217	0.6012	0.078664

Device Test: 95.21 T_RHL_MID(DHL Dead Time Mid 500kHz VIN_10V)

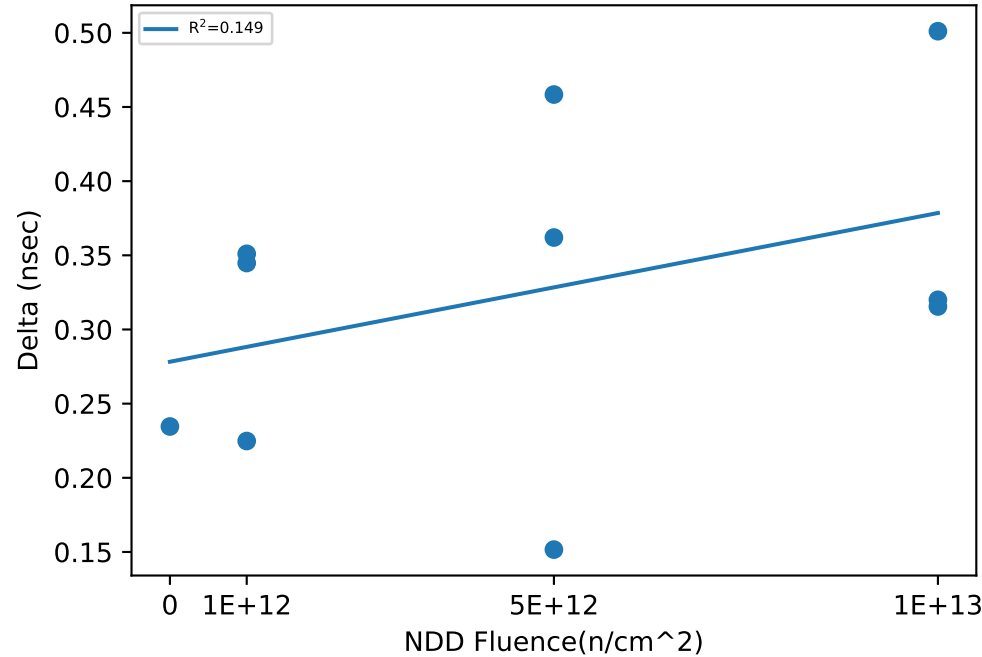
NDD vs Result Stats



Test Results (Lower Limit = 16.0, Upper Limit = 24.5 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	17.765	18.116	0.351
551	1e+12	NDD	18.181	18.526	0.3448
552	1e+12	NDD	18.546	18.77	0.2248
553	5e+12	NDD	18.116	18.574	0.4584
554	5e+12	NDD	18.119	18.481	0.362
555	5e+12	NDD	18.159	18.31	0.1516
556	1e+13	NDD	18.262	18.578	0.3155
557	1e+13	NDD	18.596	19.097	0.5011
558	1e+13	NDD	17.861	18.181	0.32
559	0	NDD, Ctrl	17.837	18.072	0.2346

NDD vs Post - Pre Exposure Delta

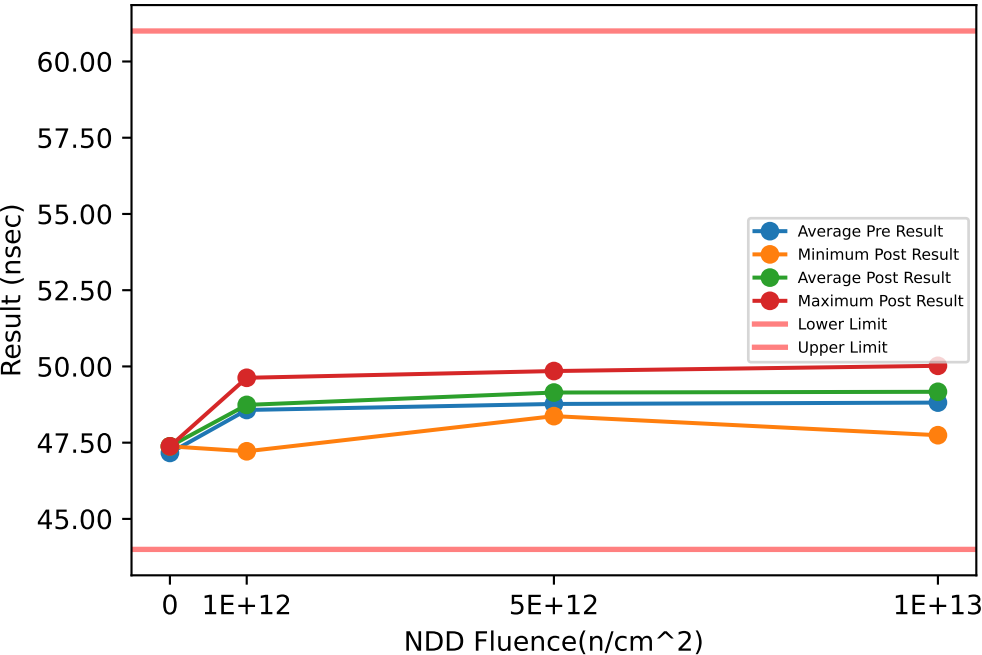


Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	17.837	17.837	17.837		18.072	18.072	18.072		0.2346	0.2346	0.2346	
1e+12	17.765	18.164	18.546	0.39038	18.116	18.471	18.77	0.33045	0.2248	0.30687	0.351	0.071139
5e+12	18.116	18.131	18.159	0.023758	18.31	18.455	18.574	0.13395	0.1516	0.324	0.4584	0.15689
1e+13	17.861	18.24	18.596	0.36752	18.181	18.619	19.097	0.45891	0.3155	0.37887	0.5011	0.10588

Device Test: 95.22 T_RHL_LARGE(DHL Dead Time Large 500kHz VIN_10V)

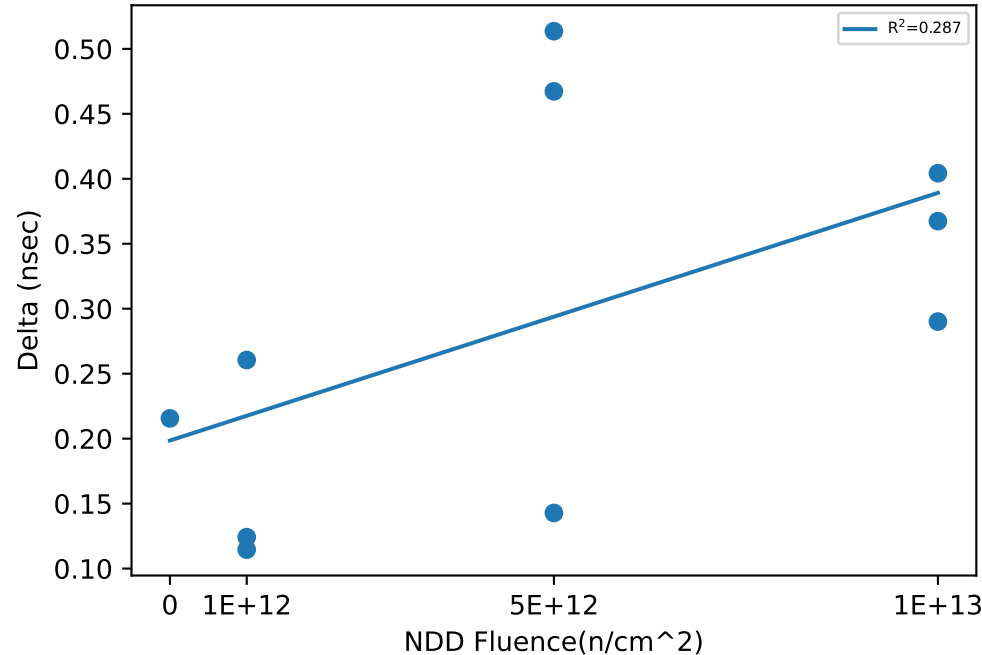
NDD vs Result Stats



Test Results (Lower Limit = 44.0, Upper Limit = 61.0 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	47.093	47.217	0.1242
551	1e+12	NDD	49.256	49.371	0.1146
552	1e+12	NDD	49.367	49.627	0.2605
553	5e+12	NDD	48.228	48.37	0.1428
554	5e+12	NDD	49.381	49.849	0.4673
555	5e+12	NDD	48.7	49.213	0.5136
556	1e+13	NDD	49.45	49.74	0.2901
557	1e+13	NDD	49.653	50.02	0.3674
558	1e+13	NDD	47.34	47.745	0.4043
559	0	NDD, Ctrl	47.164	47.38	0.2156

NDD vs Post - Pre Exposure Delta

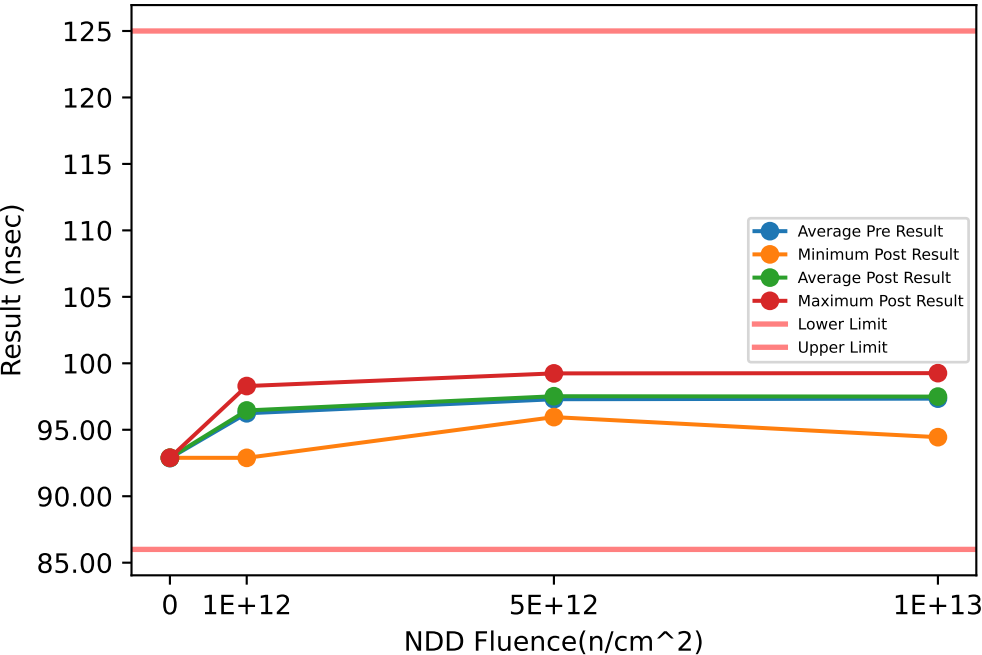


Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	47.164	47.164	47.164		47.38	47.38	47.38		0.2156	0.2156	0.2156	
1e+12	47.093	48.572	49.367	1.282	47.217	48.738	49.627	1.3236	0.1146	0.16643	0.2605	0.081605
5e+12	48.228	48.77	49.381	0.58002	48.37	49.144	49.849	0.74152	0.1428	0.37457	0.5136	0.20205
1e+13	47.34	48.814	49.653	1.2804	47.745	49.168	50.02	1.2407	0.2901	0.35393	0.4043	0.058279

Device Test: 95.23 T_RHL_MAX(DHL Dead Time Max 500kHz VIN_10V)

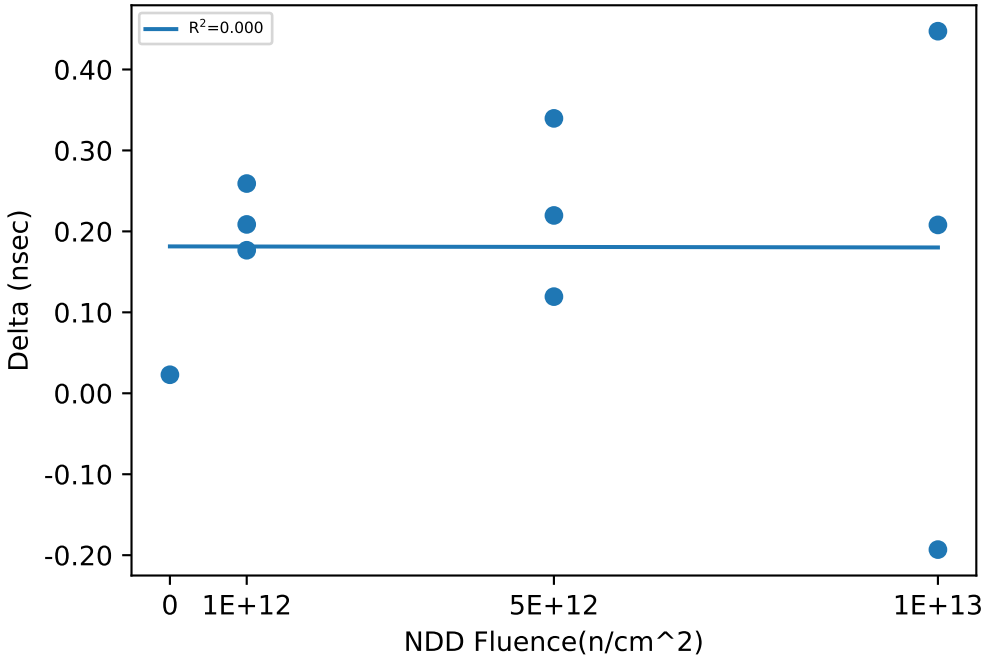
NDD vs Result Stats



Test Results (Lower Limit = 86.0, Upper Limit = 125.0 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	92.628	92.887	0.2591
551	1e+12	NDD	97.975	98.184	0.2086
552	1e+12	NDD	98.112	98.289	0.1767
553	5e+12	NDD	95.614	95.953	0.3396
554	5e+12	NDD	99.122	99.241	0.1194
555	5e+12	NDD	97.157	97.376	0.2197
556	1e+13	NDD	98.977	98.784	-0.1931
557	1e+13	NDD	98.813	99.26	0.4473
558	1e+13	NDD	94.234	94.442	0.208
559	0	NDD, Ctrl	92.868	92.891	0.0229

NDD vs Post - Pre Exposure Delta

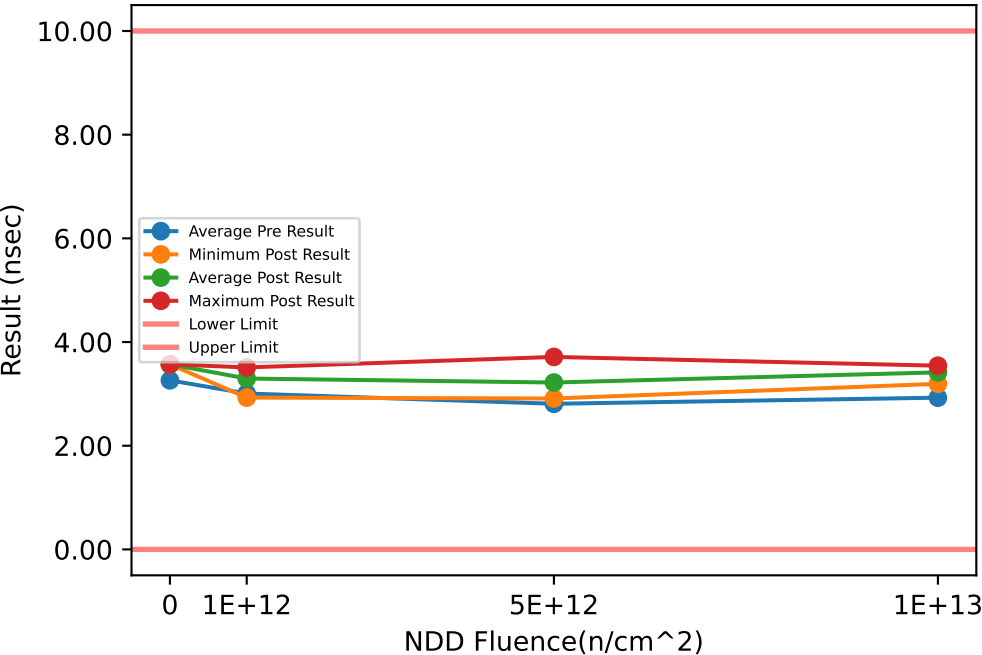


Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	92.868	92.868	92.868		92.891	92.891	92.891		0.0229	0.0229	0.0229	
1e+12	92.628	96.239	98.112	3.1275	92.887	96.453	98.289	3.0888	0.1767	0.2148	0.2591	0.041548
5e+12	95.614	97.297	99.122	1.7583	95.953	97.524	99.241	1.6489	0.1194	0.22623	0.3396	0.11025
1e+13	94.234	97.341	98.977	2.6922	94.442	97.496	99.26	2.6549	-0.1931	0.15407	0.4473	0.32359

Device Test: 95.24 T_RHL_MIN(DHL Dead Time Min 1MHz VIN_10V)

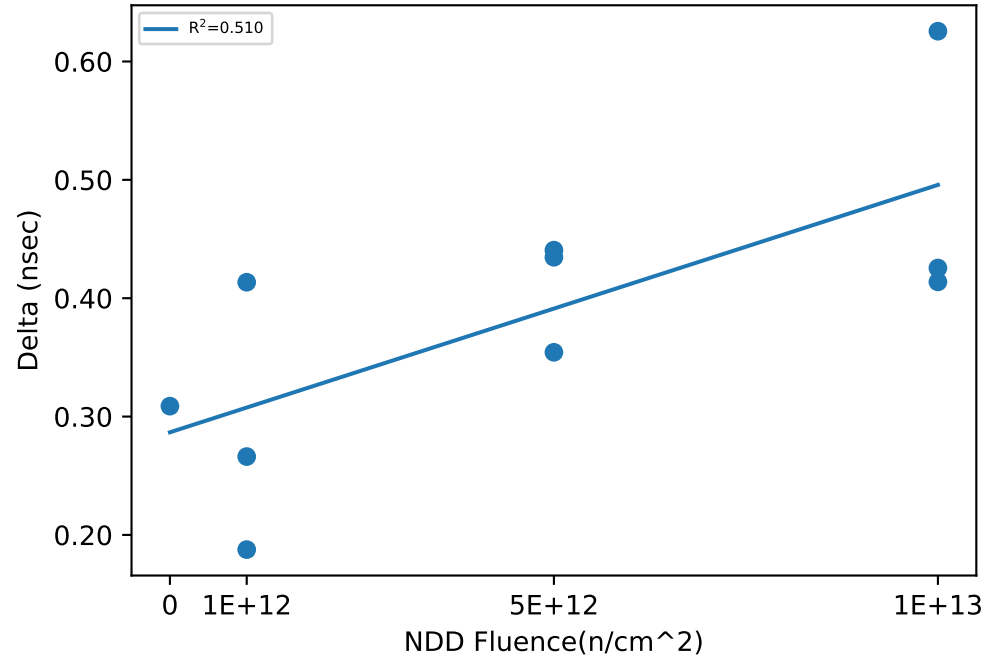
NDD vs Result Stats



Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	3.0361	3.4496	0.4135
551	1e+12	NDD	2.7405	2.9281	0.1876
552	1e+12	NDD	3.244	3.5102	0.2662
553	5e+12	NDD	3.278	3.7126	0.4346
554	5e+12	NDD	2.4705	2.9111	0.4406
555	5e+12	NDD	2.6794	3.0337	0.3543
556	1e+13	NDD	2.7801	3.1939	0.4138
557	1e+13	NDD	2.9183	3.5439	0.6256
558	1e+13	NDD	3.0813	3.5068	0.4255
559	0	NDD, Ctrl	3.2612	3.57	0.3088

NDD vs Post - Pre Exposure Delta

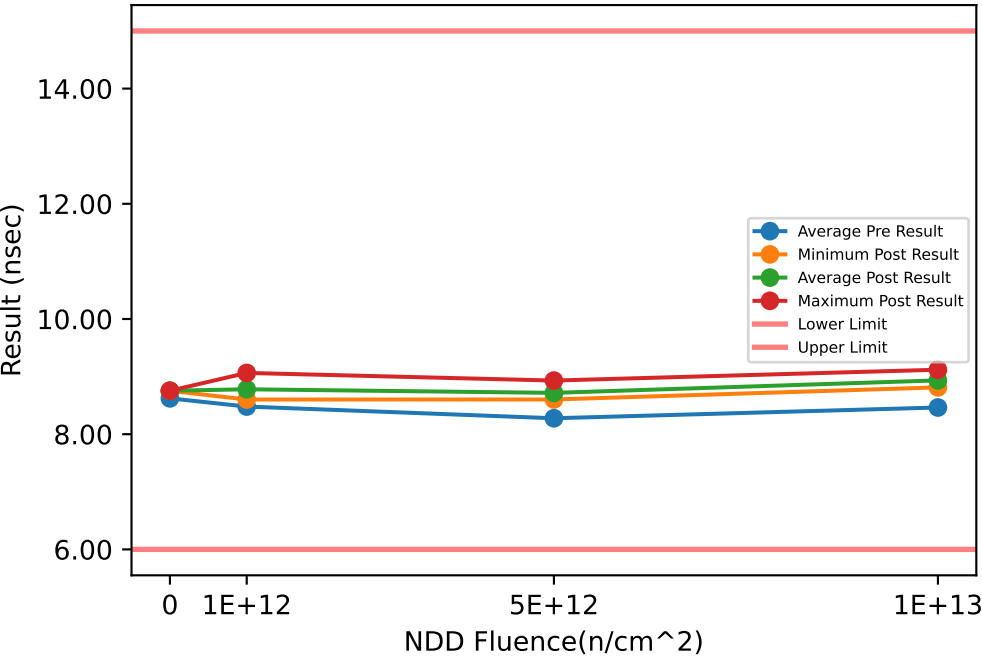


Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.2612	3.2612	3.2612		3.57	3.57	3.57		0.3088	0.3088	0.3088	
1e+12	2.7405	3.0069	3.244	0.25302	2.9281	3.296	3.5102	0.32002	0.1876	0.2891	0.4135	0.11468
5e+12	2.4705	2.8093	3.278	0.41913	2.9111	3.2191	3.7126	0.43173	0.3543	0.40983	0.4406	0.048187
1e+13	2.7801	2.9266	3.0813	0.15077	3.1939	3.4149	3.5439	0.19226	0.4138	0.4883	0.6256	0.11905

Device Test: 95.25 T_RHL_SMALL(DHL Dead Time Small 1MHz VIN_10V)

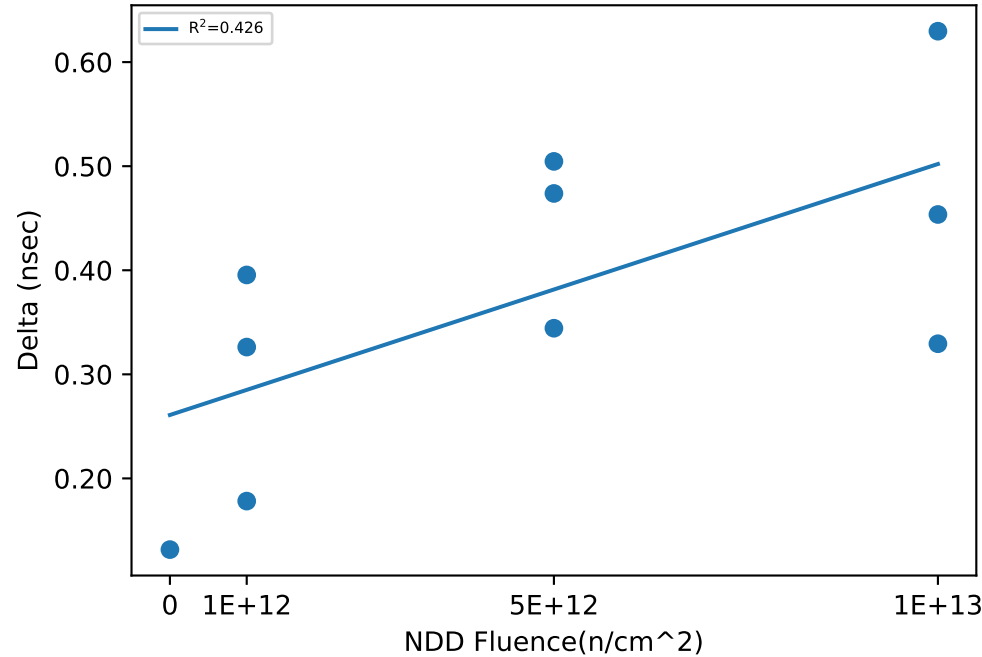
NDD vs Result Stats



Test Results (Lower Limit = 6.0, Upper Limit = 15.0 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	8.4958	8.674	0.1782
551	1e+12	NDD	8.2755	8.6017	0.3262
552	1e+12	NDD	8.6682	9.0637	0.3955
553	5e+12	NDD	8.5869	8.9312	0.3443
554	5e+12	NDD	8.0982	8.6028	0.5046
555	5e+12	NDD	8.1447	8.6185	0.4738
556	1e+13	NDD	8.4835	8.8129	0.3294
557	1e+13	NDD	8.6657	9.1193	0.4536
558	1e+13	NDD	8.2413	8.871	0.6297
559	0	NDD, Ctrl	8.6223	8.7539	0.1316

NDD vs Post - Pre Exposure Delta

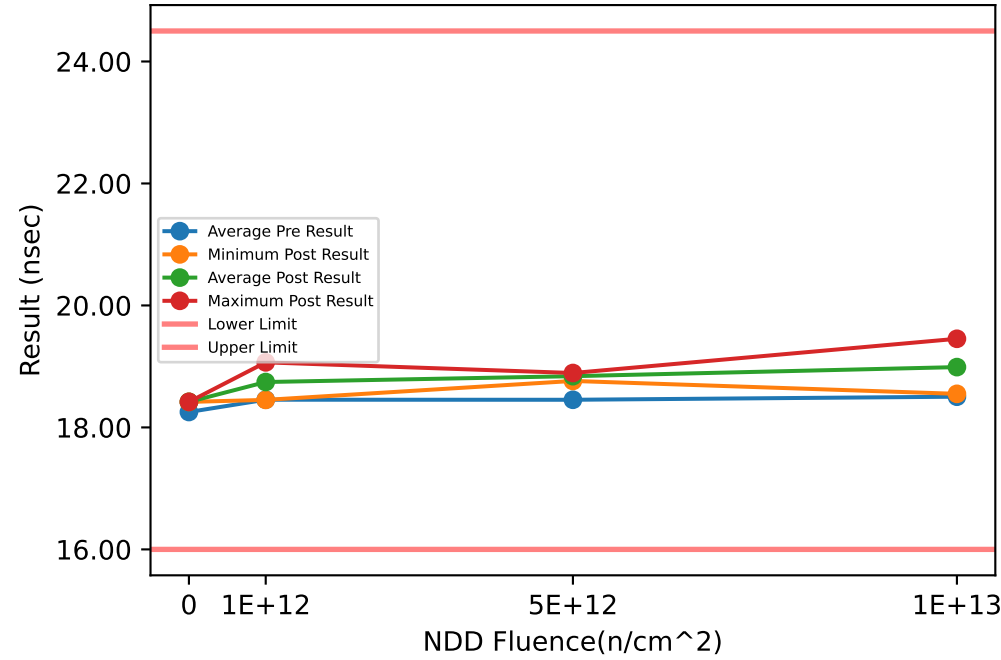


Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.6223	8.6223	8.6223		8.7539	8.7539	8.7539		0.1316	0.1316	0.1316	
1e+12	8.2755	8.4798	8.6682	0.19684	8.6017	8.7798	9.0637	0.24851	0.1782	0.29997	0.3955	0.111
5e+12	8.0982	8.2766	8.5869	0.26973	8.6028	8.7175	8.9312	0.18524	0.3443	0.4409	0.5046	0.085064
1e+13	8.2413	8.4635	8.6657	0.21291	8.8129	8.9344	9.1193	0.16274	0.3294	0.4709	0.6297	0.1509

Device Test: 95.26 T_RHL_MID(DHL Dead Time Mid 1MHz VIN_10V)

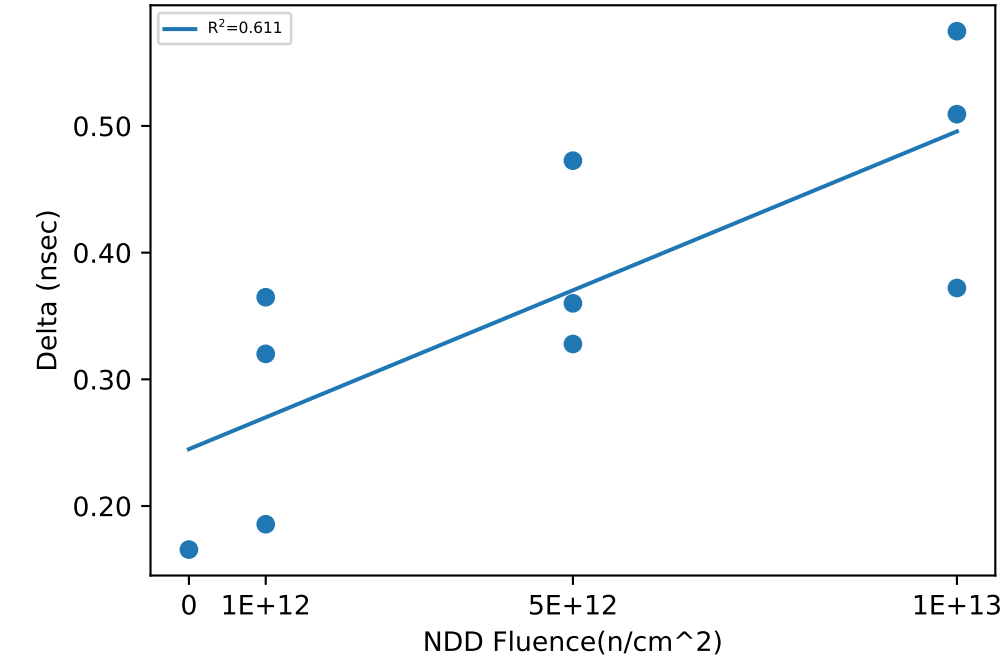
NDD vs Result Stats



Test Results (Lower Limit = 16.0, Upper Limit = 24.5 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	18.087	18.451	0.3648
551	1e+12	NDD	18.529	18.715	0.1856
552	1e+12	NDD	18.747	19.067	0.3201
553	5e+12	NDD	18.532	18.892	0.36
554	5e+12	NDD	18.538	18.866	0.3279
555	5e+12	NDD	18.289	18.762	0.4726
556	1e+13	NDD	18.591	18.963	0.3721
557	1e+13	NDD	18.878	19.453	0.5748
558	1e+13	NDD	18.041	18.551	0.5093
559	0	NDD, Ctrl	18.253	18.418	0.1656

NDD vs Post - Pre Exposure Delta

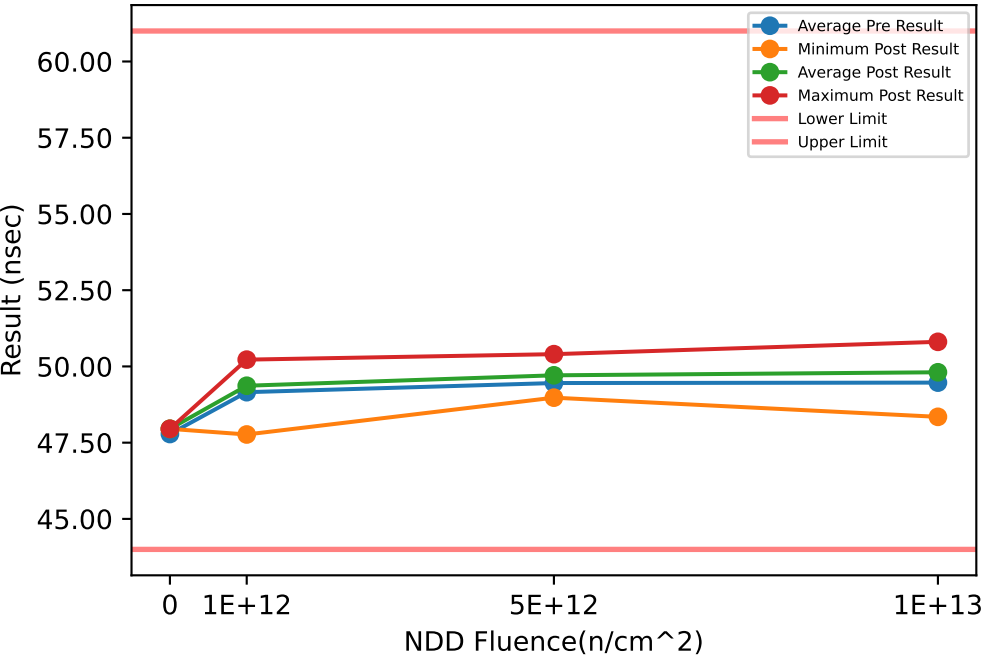


Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	18.253	18.253	18.253		18.418	18.418	18.418		0.1656	0.1656	0.1656	
1e+12	18.087	18.454	18.747	0.33638	18.451	18.744	19.067	0.30869	0.1856	0.29017	0.3648	0.093275
5e+12	18.289	18.453	18.538	0.14203	18.762	18.84	18.892	0.068941	0.3279	0.38683	0.4726	0.07599
1e+13	18.041	18.504	18.878	0.42537	18.551	18.989	19.453	0.45191	0.3721	0.4854	0.5748	0.10344

Device Test: 95.27 T_RHL_LARGE(DHL Dead Time Large 1MHz VIN_10V)

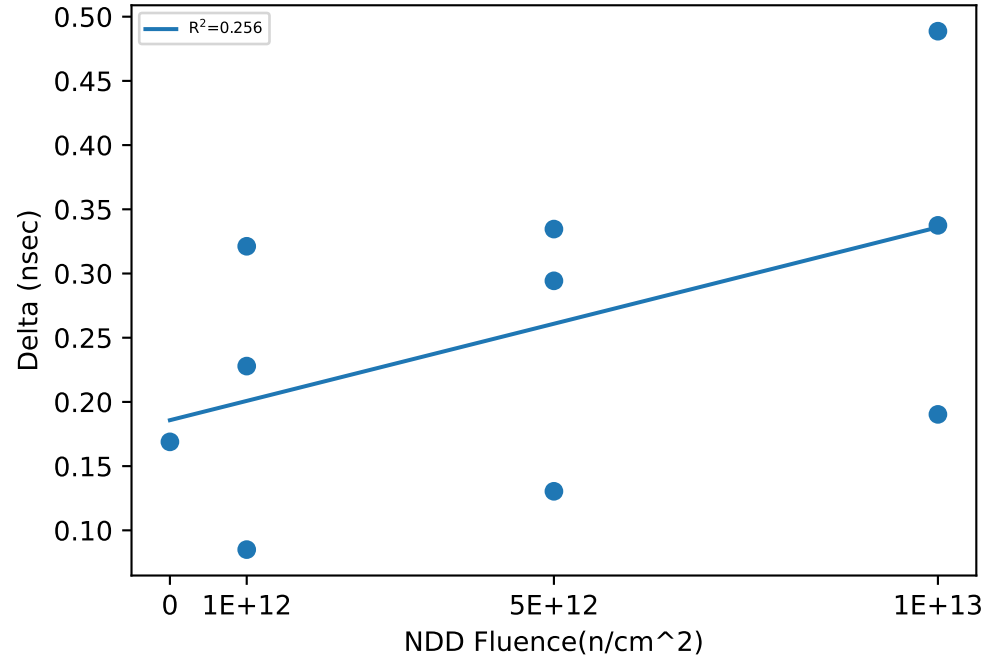
NDD vs Result Stats



Test Results (Lower Limit = 44.0, Upper Limit = 61.0 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	47.684	47.769	0.085
551	1e+12	NDD	49.882	50.109	0.2279
552	1e+12	NDD	49.902	50.223	0.3212
553	5e+12	NDD	48.845	48.976	0.1304
554	5e+12	NDD	50.068	50.402	0.3346
555	5e+12	NDD	49.454	49.748	0.2943
556	1e+13	NDD	50.081	50.271	0.1903
557	1e+13	NDD	50.318	50.807	0.4887
558	1e+13	NDD	48.01	48.347	0.3375
559	0	NDD, Ctrl	47.784	47.953	0.1689

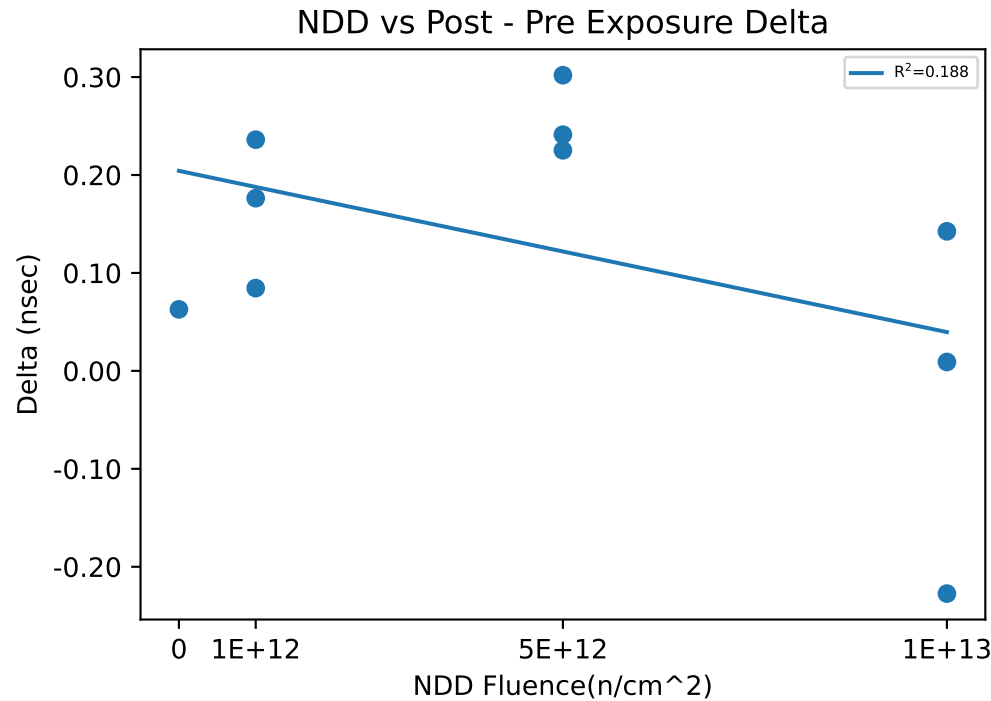
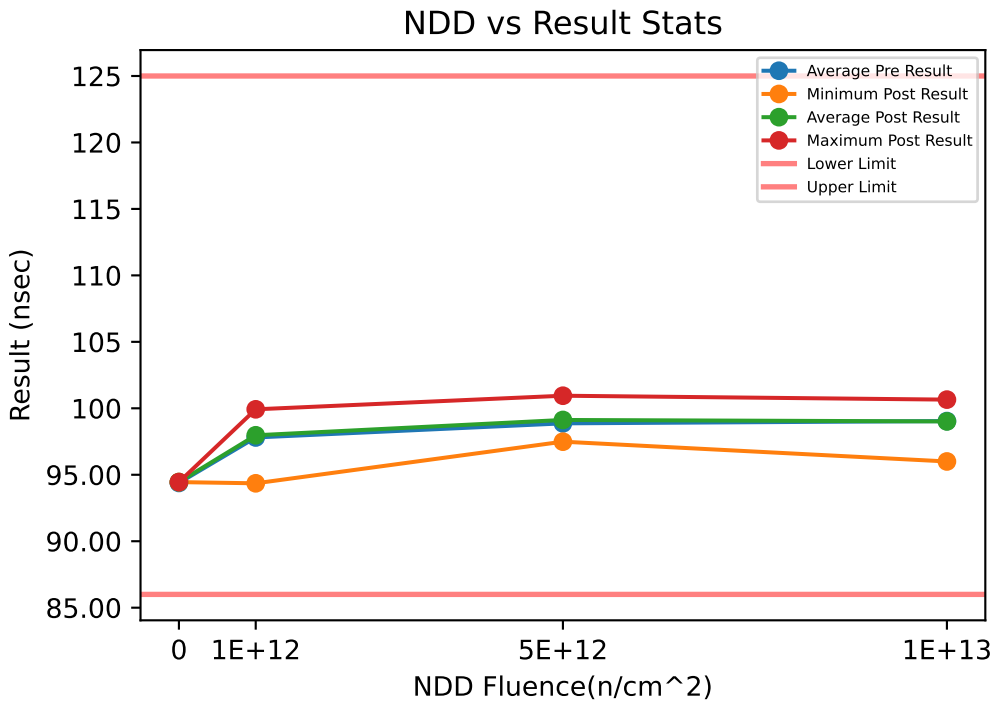
NDD vs Post - Pre Exposure Delta



Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	47.784	47.784	47.784		47.953	47.953	47.953		0.1689	0.1689	0.1689	
1e+12	47.684	49.156	49.902	1.2749	47.769	49.367	50.223	1.3854	0.085	0.21137	0.3212	0.11896
5e+12	48.845	49.456	50.068	0.61115	48.976	49.709	50.402	0.71407	0.1304	0.2531	0.3346	0.10815
1e+13	48.01	49.469	50.318	1.2699	48.347	49.808	50.807	1.2936	0.1903	0.33883	0.4887	0.1492

Device Test: 95.28 T_RHL_MAX(DHL Dead Time Max 1MHz VIN_10V)



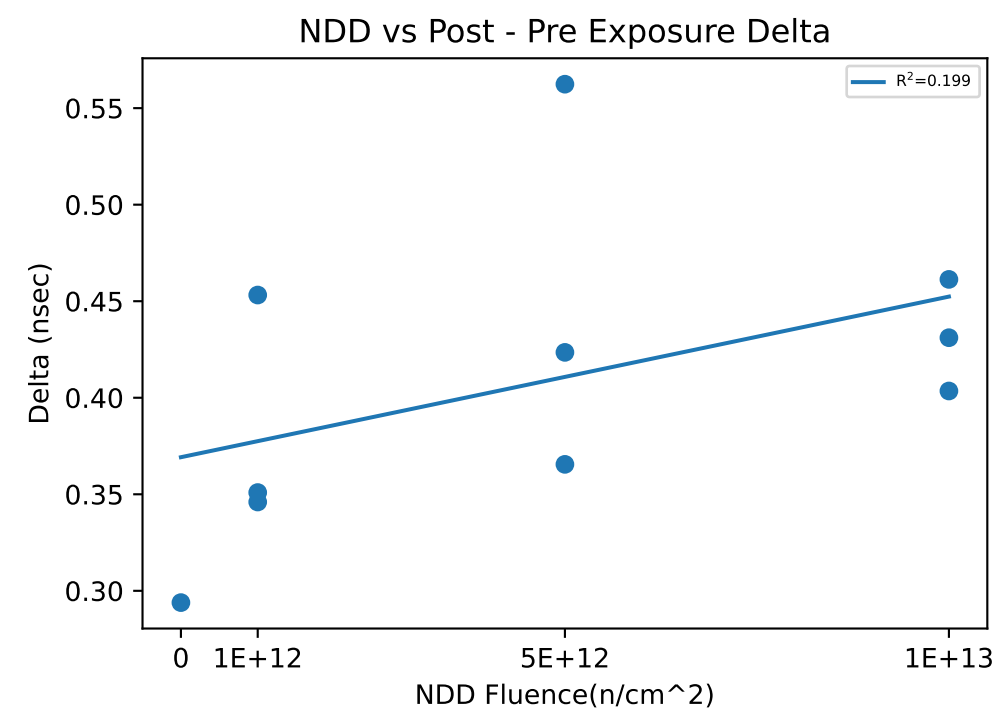
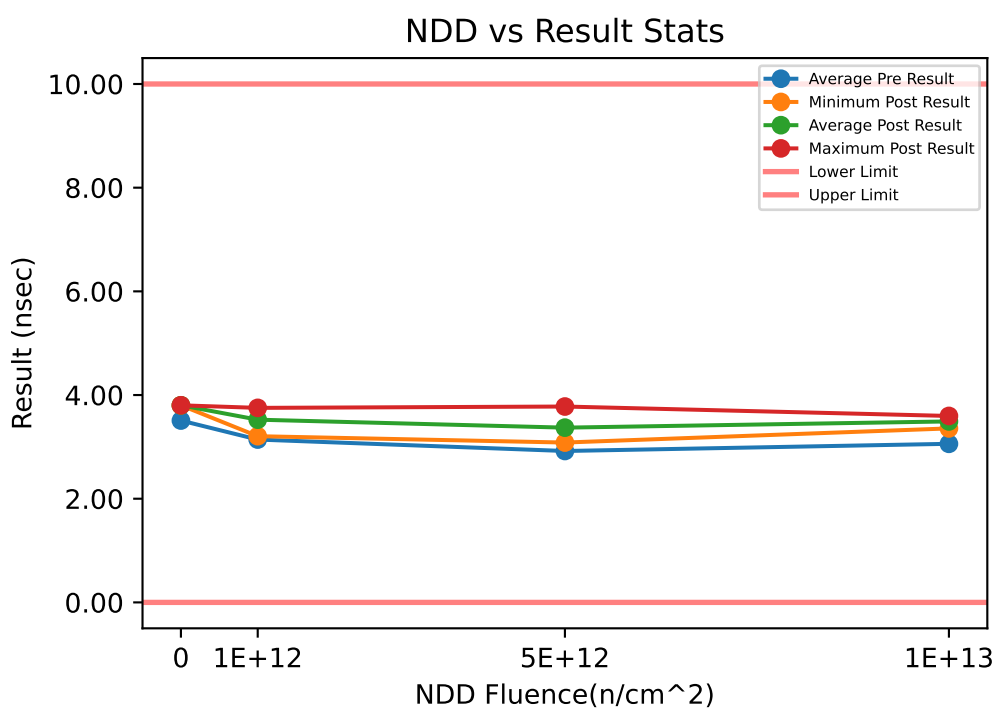
Test Results (Lower Limit = 86.0, Upper Limit = 125.0 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	94.121	94.358	0.2361
551	1e+12	NDD	99.546	99.631	0.0845
552	1e+12	NDD	99.748	99.924	0.1763
553	5e+12	NDD	97.248	97.489	0.2412
554	5e+12	NDD	100.64	100.95	0.3019
555	5e+12	NDD	98.708	98.933	0.2252
556	1e+13	NDD	100.61	100.39	-0.2274
557	1e+13	NDD	100.64	100.65	0.0091
558	1e+13	NDD	95.858	96.001	0.1425
559	0	NDD, Ctrl	94.385	94.448	0.0628

Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	94.385	94.385	94.385		94.448	94.448	94.448		0.0628	0.0628	0.0628	
1e+12	94.121	97.805	99.748	3.1917	94.358	97.971	99.924	3.1325	0.0845	0.16563	0.2361	0.076361
5e+12	97.248	98.867	100.64	1.7039	97.489	99.123	100.95	1.7364	0.2252	0.2561	0.3019	0.040463
1e+13	95.858	99.039	100.64	2.7545	96.001	99.014	100.65	2.6126	-0.2274	-0.025267	0.1425	0.18733

Device Test: 95.29 T_RHL_MIN(DHL Dead Time Min 2MHz VIN_10V)



Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (nsec))

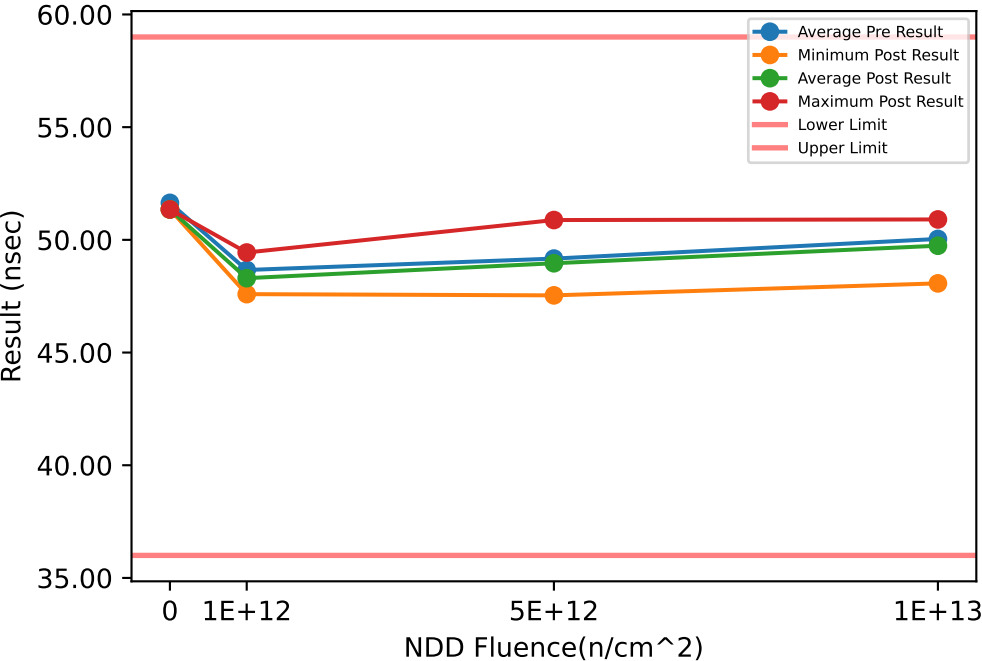
Serial #	Fluence(n/cm ²)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	3.2644	3.6153	0.3509
551	1e+12	NDD	2.8602	3.2062	0.346
552	1e+12	NDD	3.2992	3.7524	0.4532
553	5e+12	NDD	3.4129	3.7784	0.3655
554	5e+12	NDD	2.66	3.0835	0.4235
555	5e+12	NDD	2.6888	3.2512	0.5624
556	1e+13	NDD	2.9528	3.3563	0.4035
557	1e+13	NDD	3.0589	3.5202	0.4613
558	1e+13	NDD	3.1656	3.5967	0.4311
559	0	NDD, Ctrl	3.5081	3.802	0.2939

Test Statistics (nsec)

Fluence(n/cm ²)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.5081	3.5081	3.5081		3.802	3.802	3.802		0.2939	0.2939	0.2939	
1e+12	2.8602	3.1413	3.2992	0.24403	3.2062	3.5246	3.7524	0.28416	0.346	0.38337	0.4532	0.060527
5e+12	2.66	2.9206	3.4129	0.42662	3.0835	3.371	3.7784	0.36262	0.3655	0.45047	0.5624	0.10118
1e+13	2.9528	3.0591	3.1656	0.1064	3.3563	3.4911	3.5967	0.12282	0.4035	0.43197	0.4613	0.02891

Device Test: 95.3 T_RLH_LARGE(DLH Dead Time Large 500kHz VIN_10V)

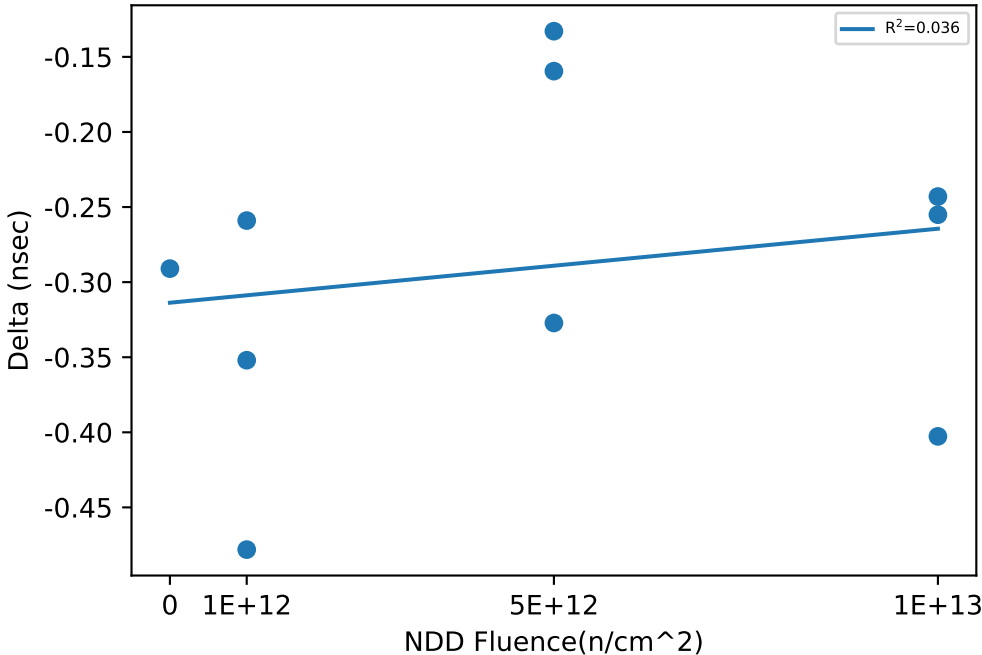
NDD vs Result Stats



Test Results (Lower Limit = 36.0, Upper Limit = 59.0 (nsec))

Serial #	Fluence(n/cm ²)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	48.221	47.869	-0.352
551	1e+12	NDD	48.07	47.592	-0.4781
552	1e+12	NDD	49.697	49.438	-0.259
553	5e+12	NDD	48.628	48.469	-0.1595
554	5e+12	NDD	47.864	47.537	-0.3272
555	5e+12	NDD	51.012	50.879	-0.1329
556	1e+13	NDD	48.312	48.069	-0.243
557	1e+13	NDD	51.16	50.905	-0.2551
558	1e+13	NDD	50.648	50.245	-0.4027
559	0	NDD, Ctrl	51.64	51.349	-0.291

NDD vs Post - Pre Exposure Delta

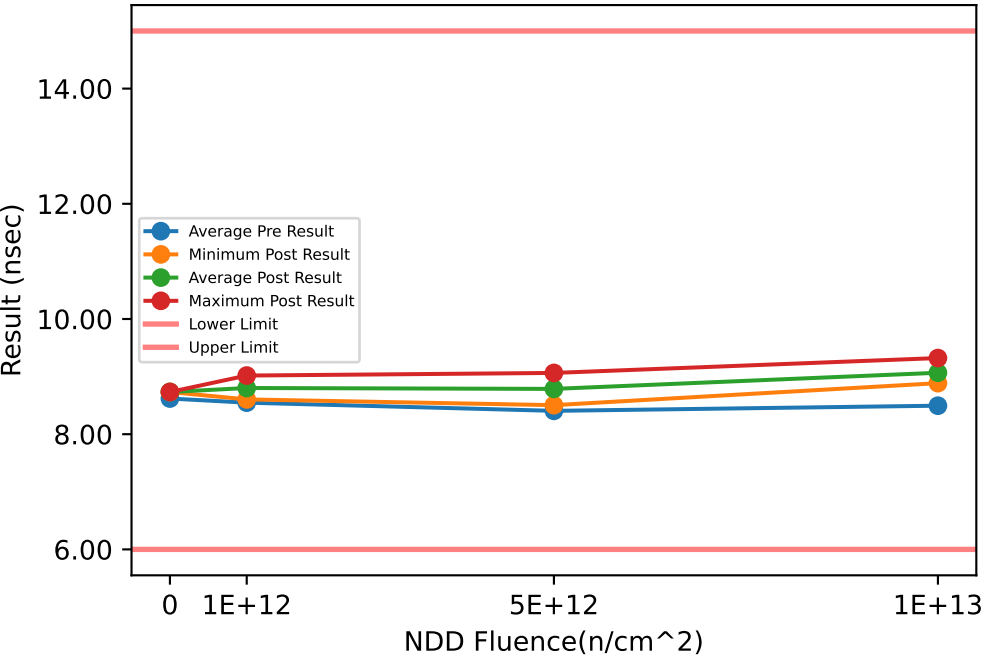


Test Statistics (nsec)

Fluence(n/cm ²)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	51.64	51.64	51.64		51.349	51.349	51.349		-0.291	-0.291	-0.291	
1e+12	48.07	48.663	49.697	0.89898	47.592	48.3	49.438	0.99559	-0.4781	-0.36303	-0.259	0.10997
5e+12	47.864	49.168	51.012	1.6417	47.537	48.962	50.879	1.7245	-0.3272	-0.20653	-0.1329	0.10534
1e+13	48.312	50.04	51.16	1.5183	48.069	49.74	50.905	1.4841	-0.4027	-0.30027	-0.243	0.088916

Device Test: 95.30 T_RHL_SMALL(DHL Dead Time Small 2MHz VIN_10V)

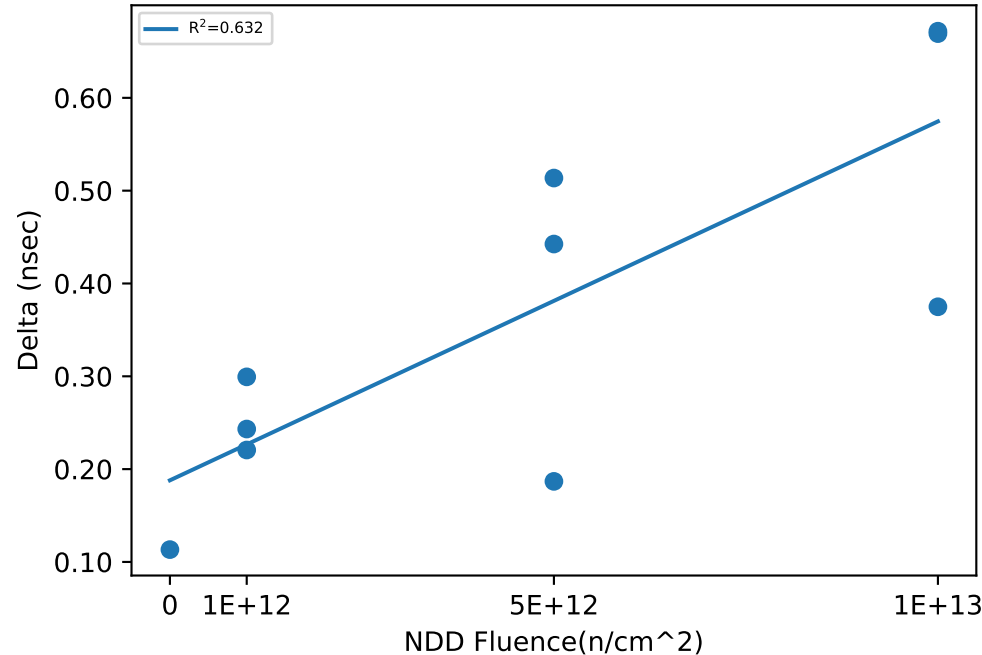
NDD vs Result Stats



Test Results (Lower Limit = 6.0, Upper Limit = 15.0 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	8.4844	8.7838	0.2994
551	1e+12	NDD	8.3608	8.604	0.2432
552	1e+12	NDD	8.7975	9.0181	0.2206
553	5e+12	NDD	8.6211	9.0636	0.4425
554	5e+12	NDD	8.2778	8.7914	0.5136
555	5e+12	NDD	8.3173	8.5041	0.1868
556	1e+13	NDD	8.5113	8.8862	0.3749
557	1e+13	NDD	8.65	9.3218	0.6718
558	1e+13	NDD	8.3228	8.992	0.6692
559	0	NDD, Ctrl	8.6192	8.7325	0.1133

NDD vs Post - Pre Exposure Delta

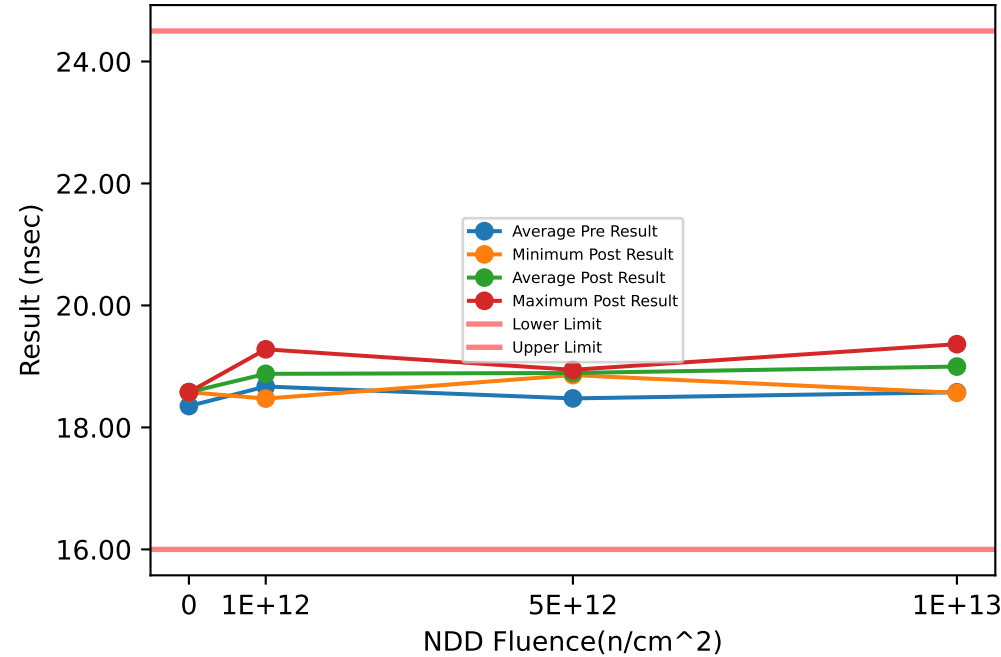


Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.6192	8.6192	8.6192		8.7325	8.7325	8.7325		0.1133	0.1133	0.1133	
1e+12	8.3608	8.5476	8.7975	0.2251	8.604	8.802	9.0181	0.20765	0.2206	0.2544	0.2994	0.040576
5e+12	8.2778	8.4054	8.6211	0.18784	8.5041	8.7864	9.0636	0.27978	0.1868	0.38097	0.5136	0.17187
1e+13	8.3228	8.4947	8.65	0.16423	8.8862	9.0667	9.3218	0.2272	0.3749	0.57197	0.6718	0.17067

Device Test: 95.31 T_RHL_MID(DHL Dead Time Mid 2MHz VIN_10V)

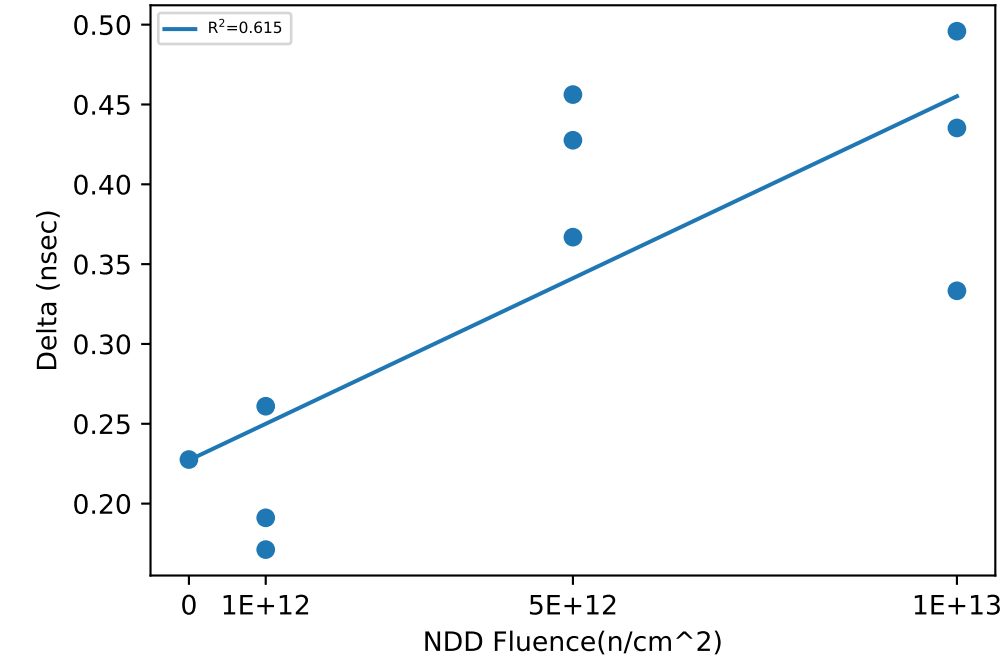
NDD vs Result Stats



Test Results (Lower Limit = 16.0, Upper Limit = 24.5 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	18.301	18.473	0.1712
551	1e+12	NDD	18.691	18.883	0.1911
552	1e+12	NDD	19.02	19.281	0.261
553	5e+12	NDD	18.488	18.944	0.4562
554	5e+12	NDD	18.509	18.876	0.3669
555	5e+12	NDD	18.43	18.858	0.4276
556	1e+13	NDD	18.728	19.061	0.3333
557	1e+13	NDD	18.93	19.365	0.4353
558	1e+13	NDD	18.072	18.568	0.4959
559	0	NDD, Ctrl	18.351	18.578	0.2276

NDD vs Post - Pre Exposure Delta

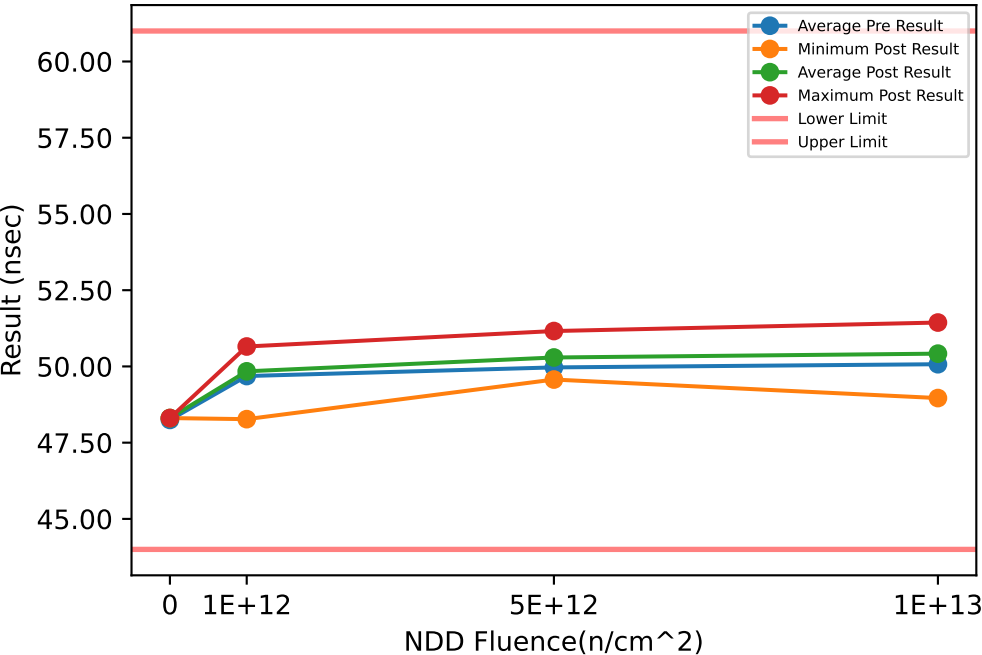


Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	18.351	18.351	18.351		18.578	18.578	18.578		0.2276	0.2276	0.2276	
1e+12	18.301	18.671	19.02	0.35964	18.473	18.879	19.281	0.40411	0.1712	0.20777	0.261	0.047163
5e+12	18.43	18.476	18.509	0.040726	18.858	18.893	18.944	0.045603	0.3669	0.4169	0.4562	0.045601
1e+13	18.072	18.576	18.93	0.44862	18.568	18.998	19.365	0.40243	0.3333	0.4215	0.4959	0.082174

Device Test: 95.32 T_RHL_LARGE(DHL Dead Time Large 2MHz VIN_10V)

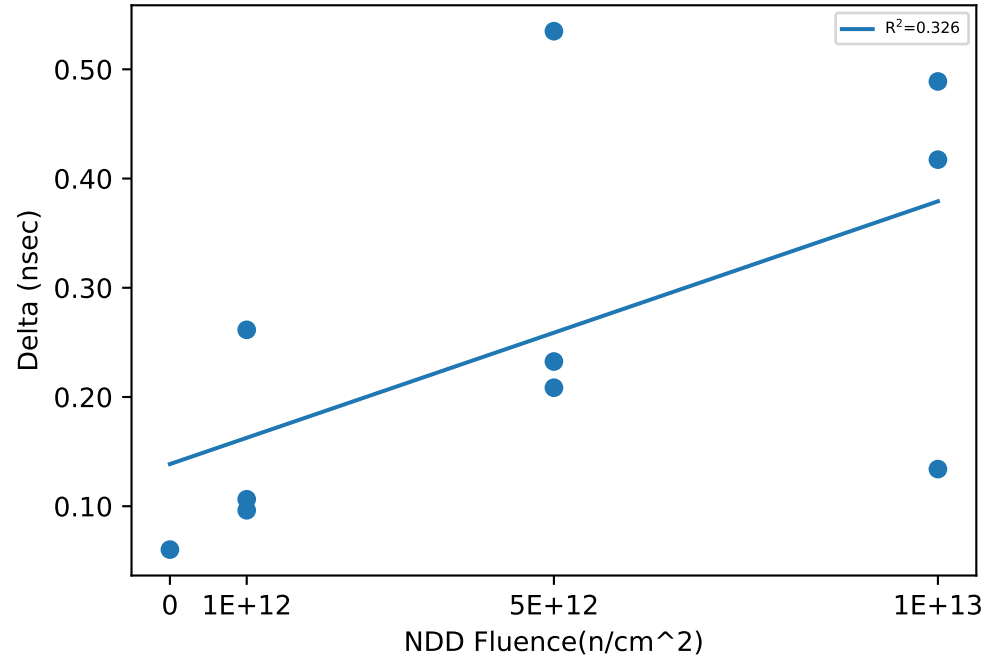
NDD vs Result Stats



Test Results (Lower Limit = 44.0, Upper Limit = 61.0 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	48.165	48.271	0.1064
551	1e+12	NDD	50.497	50.594	0.0963
552	1e+12	NDD	50.392	50.654	0.2615
553	5e+12	NDD	49.338	49.57	0.2325
554	5e+12	NDD	50.626	51.161	0.5349
555	5e+12	NDD	49.941	50.149	0.2085
556	1e+13	NDD	50.721	50.855	0.134
557	1e+13	NDD	50.95	51.439	0.4889
558	1e+13	NDD	48.545	48.963	0.4173
559	0	NDD, Ctrl	48.246	48.306	0.0603

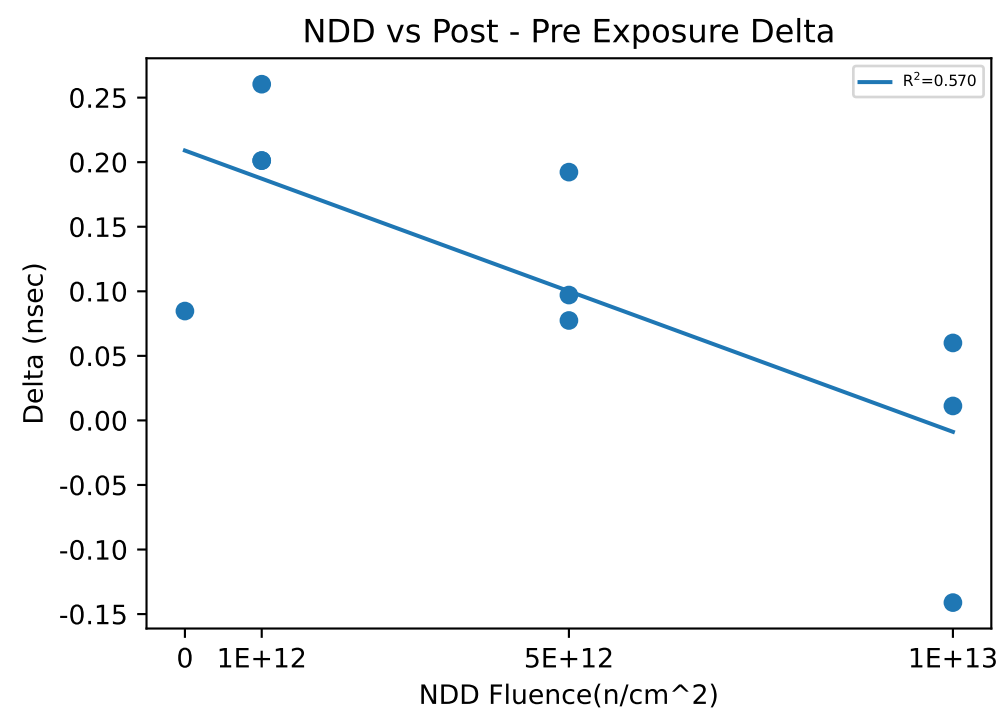
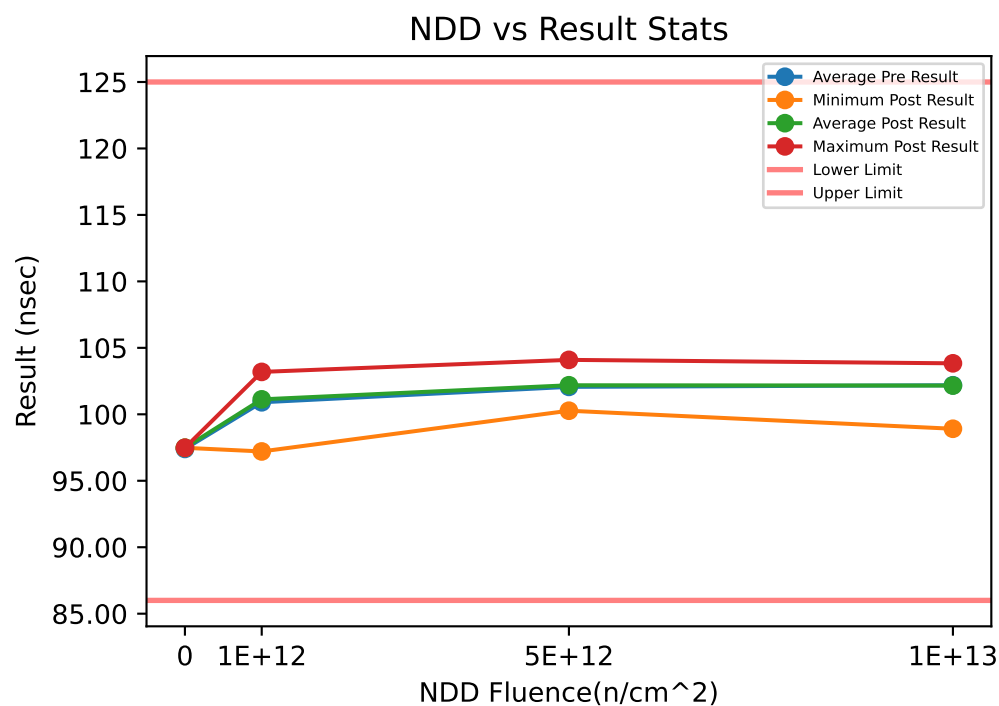
NDD vs Post - Pre Exposure Delta



Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	48.246	48.246	48.246		48.306	48.306	48.306		0.0603	0.0603	0.0603	
1e+12	48.165	49.685	50.497	1.3174	48.271	49.839	50.654	1.3586	0.0963	0.15473	0.2615	0.0926
5e+12	49.338	49.968	50.626	0.64453	49.57	50.293	51.161	0.80503	0.2085	0.3253	0.5349	0.18192
1e+13	48.545	50.072	50.95	1.3274	48.963	50.419	51.439	1.2947	0.134	0.34673	0.4889	0.18768

Device Test: 95.33 T_RHL_MAX(DHL Dead Time Max 2MHz VIN_10V)



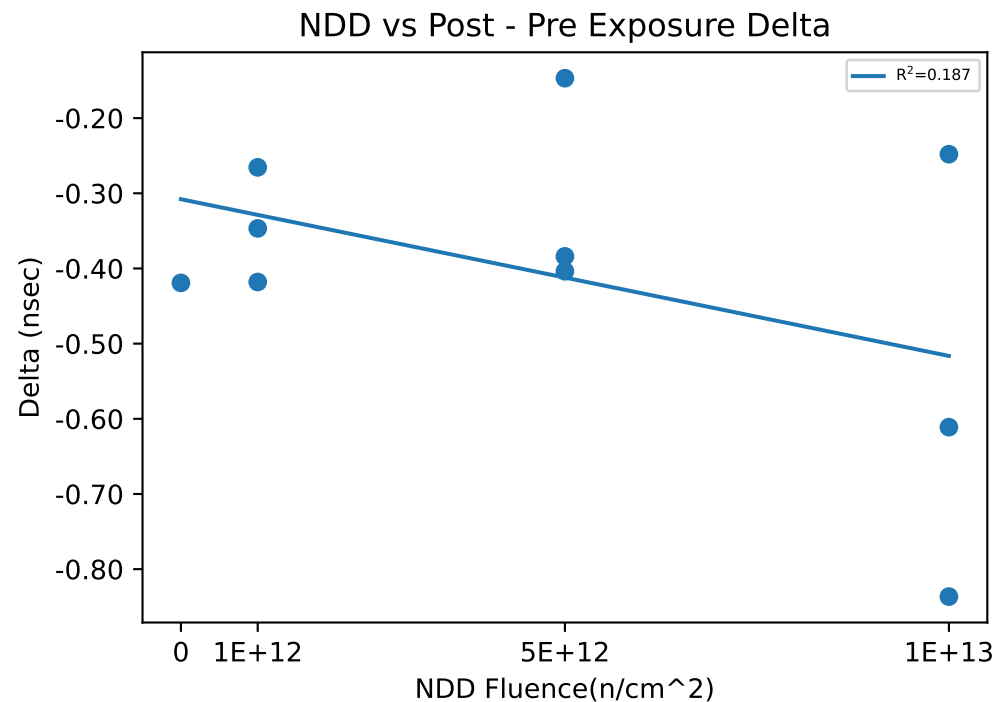
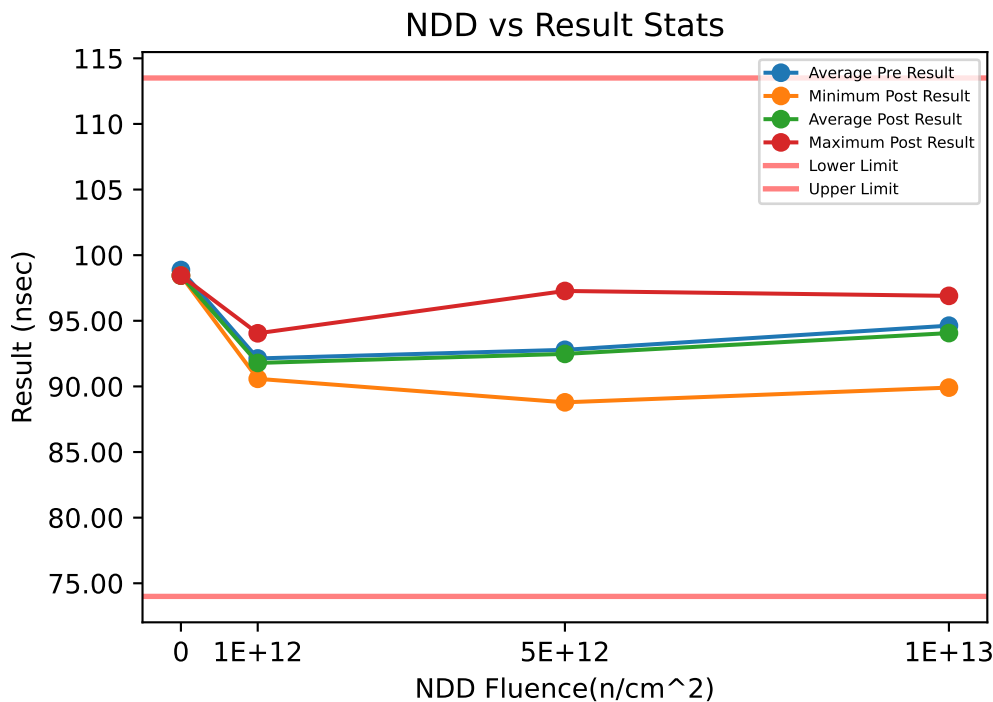
Test Results (Lower Limit = 86.0, Upper Limit = 125.0 (nsec))

Serial #	Fluence(n/cm ²)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	96.945	97.205	0.2604
551	1e+12	NDD	102.78	102.98	0.2012
552	1e+12	NDD	102.99	103.19	0.2013
553	5e+12	NDD	100.17	100.27	0.0971
554	5e+12	NDD	104.02	104.09	0.0774
555	5e+12	NDD	102	102.19	0.1923
556	1e+13	NDD	103.88	103.74	-0.1411
557	1e+13	NDD	103.78	103.84	0.06
558	1e+13	NDD	98.901	98.913	0.0112
559	0	NDD, Ctrl	97.395	97.48	0.0847

Test Statistics (nsec)

Fluence(n/cm ²)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	97.395	97.395	97.395		97.48	97.48	97.48		0.0847	0.0847	0.0847	
1e+12	96.945	100.9	102.99	3.4304	97.205	101.13	103.19	3.3963	0.2012	0.22097	0.2604	0.03415
5e+12	100.17	102.06	104.02	1.923	100.27	102.19	104.09	1.9124	0.0774	0.12227	0.1923	0.061445
1e+13	98.901	102.19	103.88	2.8441	98.913	102.16	103.84	2.8142	-0.1411	-0.0233	0.06	0.1049

Device Test: 95.4 T_RLH_MAX(DLH Dead Time Max 500kHz VIN_10V)



Test Results (Lower Limit = 74.0, Upper Limit = 113.5 (nsec))

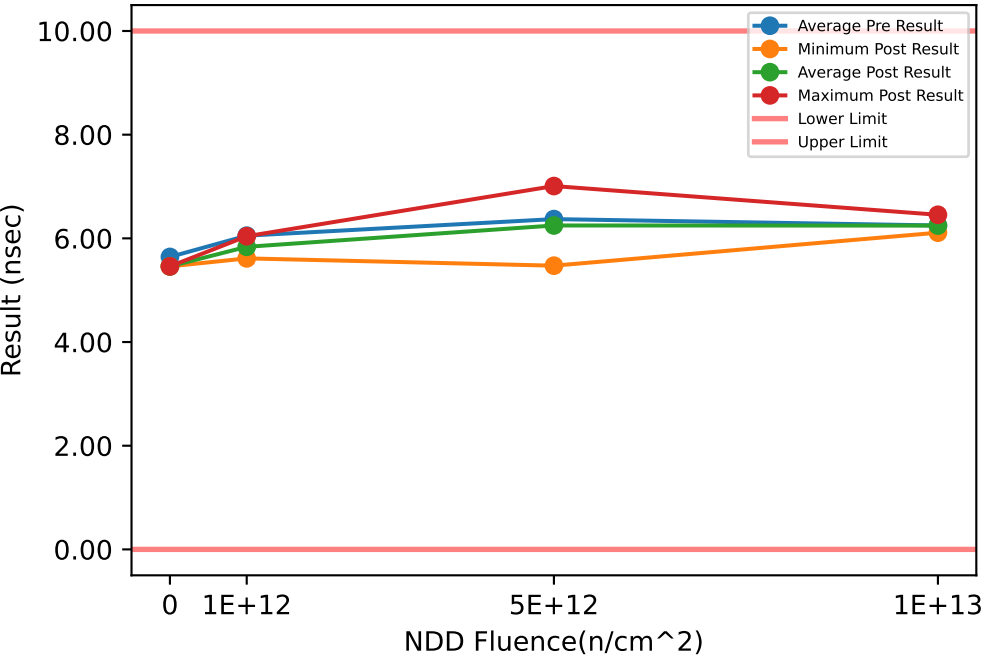
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	91.005	90.739	-0.2655
551	1e+12	NDD	90.925	90.579	-0.3467
552	1e+12	NDD	94.465	94.047	-0.418
553	5e+12	NDD	91.518	91.371	-0.1469
554	5e+12	NDD	89.191	88.787	-0.4037
555	5e+12	NDD	97.657	97.273	-0.3839
556	1e+13	NDD	90.157	89.909	-0.248
557	1e+13	NDD	97.511	96.9	-0.6111
558	1e+13	NDD	96.216	95.379	-0.8365
559	0	NDD, Ctrl	98.869	98.45	-0.4192

Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	98.869	98.869	98.869		98.45	98.45	98.45		-0.4192	-0.4192	-0.4192	
1e+12	90.925	92.132	94.465	2.0211	90.579	91.788	94.047	1.9578	-0.418	-0.3434	-0.2655	0.076304
5e+12	89.191	92.788	97.657	4.3736	88.787	92.477	97.273	4.3496	-0.4037	-0.3115	-0.1469	0.14289
1e+13	90.157	94.628	97.511	3.9257	89.909	94.063	96.9	3.6767	-0.8365	-0.5652	-0.248	0.29692

Device Test: 95.5 T_RLH_MIN(DLH Dead Time Min 1MHz VIN_10V)

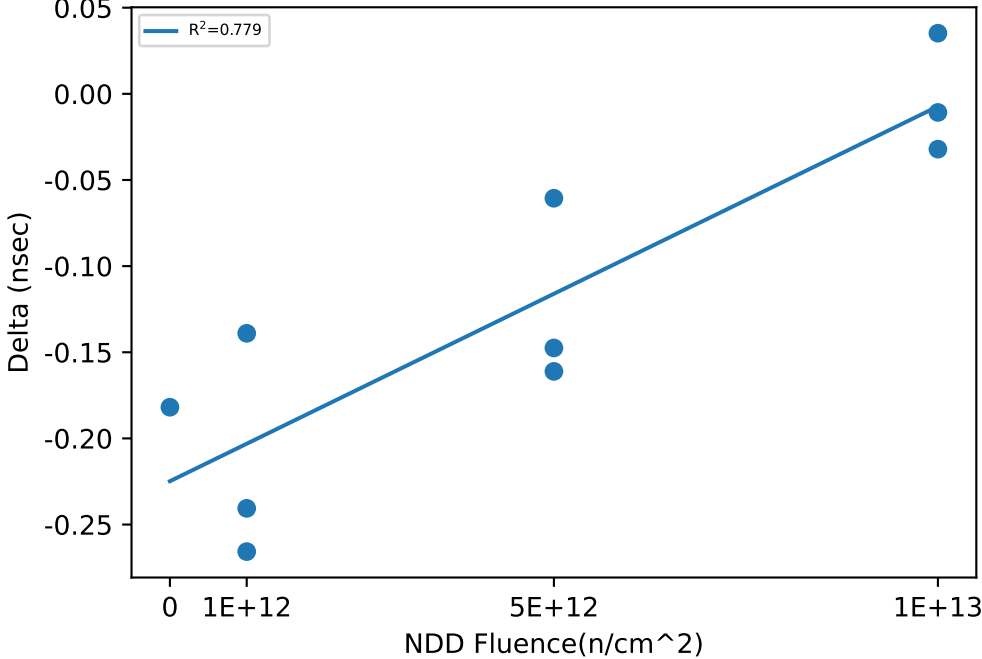
NDD vs Result Stats



Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	6.3066	6.0409	-0.2657
551	1e+12	NDD	5.9941	5.8551	-0.139
552	1e+12	NDD	5.8544	5.6138	-0.2406
553	5e+12	NDD	6.3237	6.2631	-0.0606
554	5e+12	NDD	7.17	7.0089	-0.1611
555	5e+12	NDD	5.6205	5.473	-0.1475
556	1e+13	NDD	6.4197	6.4549	0.0352
557	1e+13	NDD	6.1416	6.1095	-0.0321
558	1e+13	NDD	6.1848	6.174	-0.0108
559	0	NDD, Ctrl	5.6414	5.4595	-0.1819

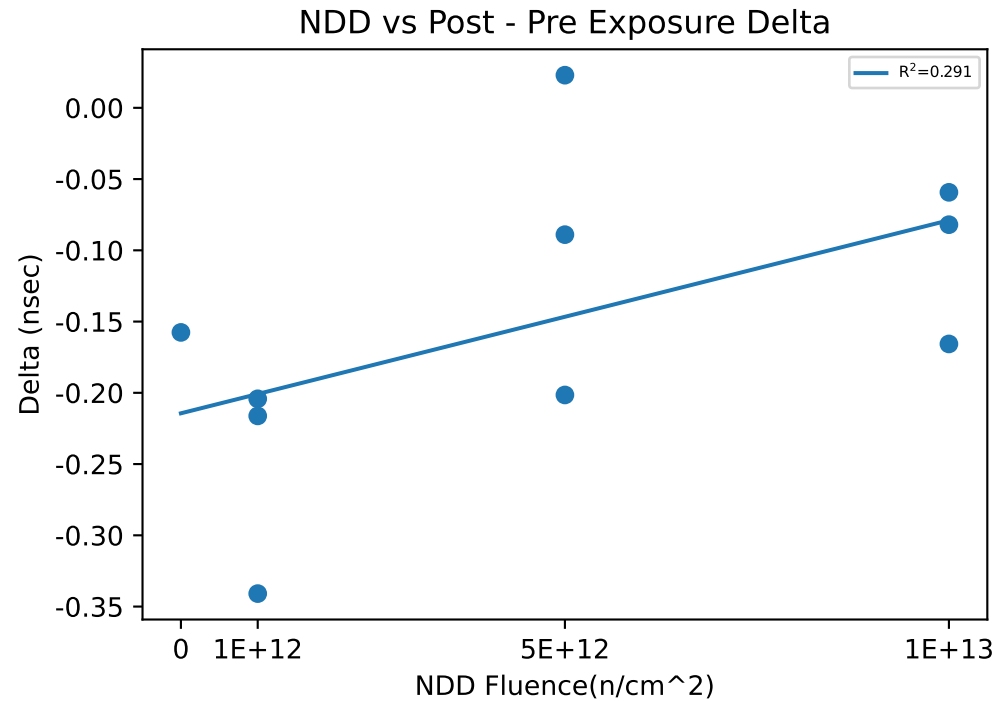
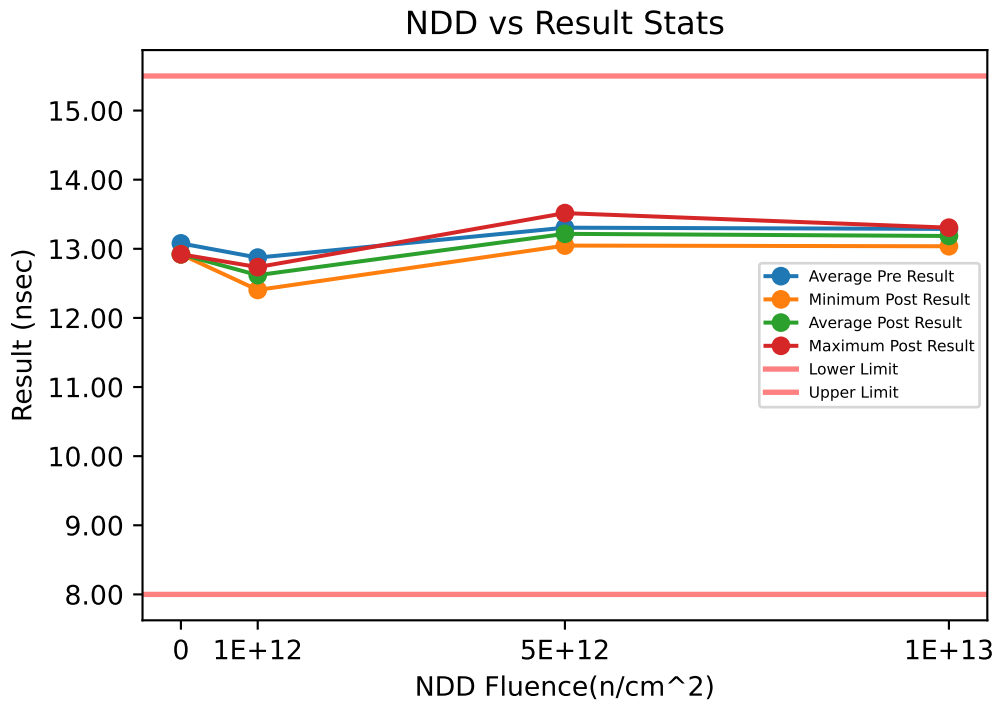
NDD vs Post - Pre Exposure Delta



Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.6414	5.6414	5.6414		5.4595	5.4595	5.4595		-0.1819	-0.1819	-0.1819	
1e+12	5.8544	6.0517	6.3066	0.23154	5.6138	5.8366	6.0409	0.21415	-0.2657	-0.2151	-0.139	0.067089
5e+12	5.6205	6.3714	7.17	0.77585	5.473	6.2483	7.0089	0.76806	-0.1611	-0.12307	-0.0606	0.054523
1e+13	6.1416	6.2487	6.4197	0.14966	6.1095	6.2461	6.4549	0.18365	-0.0321	-0.0025667	0.0352	0.034397

Device Test: 95.6 T_RLH_SMALL(DLH Dead Time Small 1MHz VIN_10V)



Test Results (Lower Limit = 8.0, Upper Limit = 15.5 (nsec))

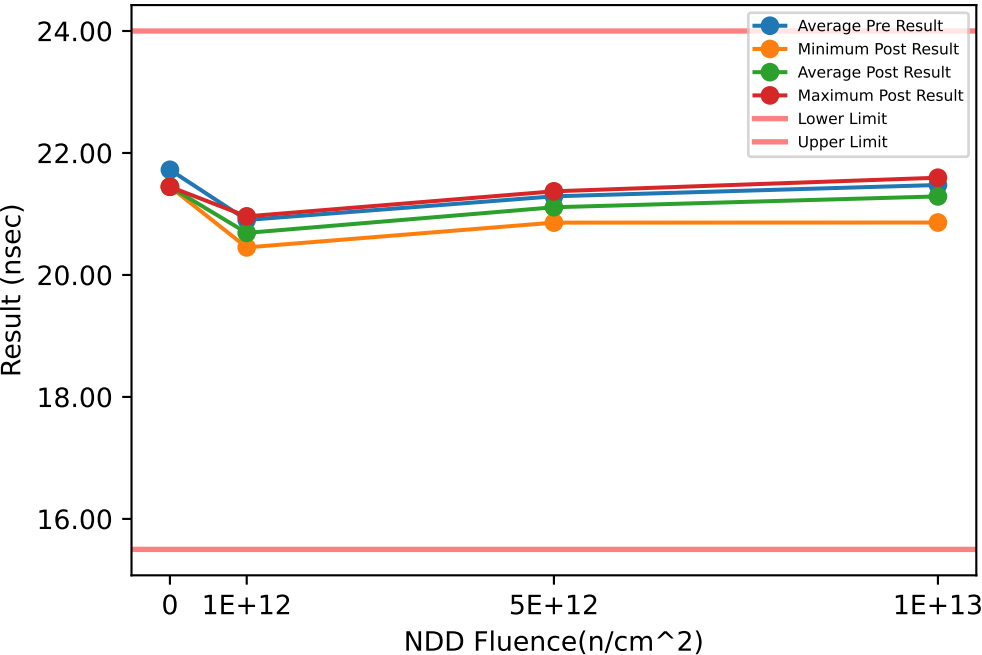
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	12.939	12.735	-0.2042
551	1e+12	NDD	12.745	12.405	-0.3409
552	1e+12	NDD	12.933	12.717	-0.2162
553	5e+12	NDD	13.175	13.086	-0.089
554	5e+12	NDD	13.718	13.516	-0.2015
555	5e+12	NDD	13.024	13.046	0.0229
556	1e+13	NDD	13.119	13.037	-0.082
557	1e+13	NDD	13.365	13.306	-0.0593
558	1e+13	NDD	13.379	13.214	-0.1657
559	0	NDD, Ctrl	13.079	12.921	-0.1576

Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	13.079	13.079	13.079		12.921	12.921	12.921		-0.1576	-0.1576	-0.1576	
1e+12	12.745	12.873	12.939	0.11023	12.405	12.619	12.735	0.18586	-0.3409	-0.25377	-0.2042	0.075698
5e+12	13.024	13.305	13.718	0.36503	13.046	13.216	13.516	0.26059	-0.2015	-0.0892	0.0229	0.1122
1e+13	13.119	13.288	13.379	0.14656	13.037	13.185	13.306	0.13676	-0.1657	-0.10233	-0.0593	0.056039

Device Test: 95.7 T_RLH_MID(DLH Dead Time Mid 1MHz VIN_10V)

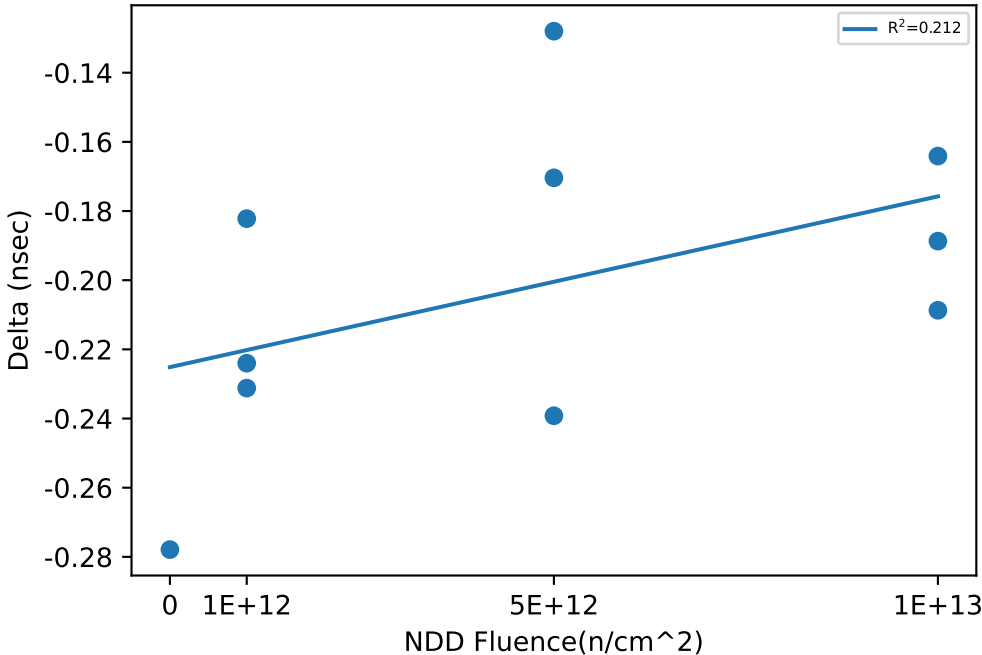
NDD vs Result Stats



Test Results (Lower Limit = 15.5, Upper Limit = 24.0 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	20.838	20.656	-0.1822
551	1e+12	NDD	20.676	20.452	-0.224
552	1e+12	NDD	21.192	20.96	-0.2312
553	5e+12	NDD	21.097	20.858	-0.2392
554	5e+12	NDD	21.228	21.1	-0.128
555	5e+12	NDD	21.542	21.371	-0.1704
556	1e+13	NDD	21.068	20.86	-0.2087
557	1e+13	NDD	21.759	21.594	-0.1641
558	1e+13	NDD	21.598	21.409	-0.1887
559	0	NDD, Ctrl	21.724	21.446	-0.2779

NDD vs Post - Pre Exposure Delta

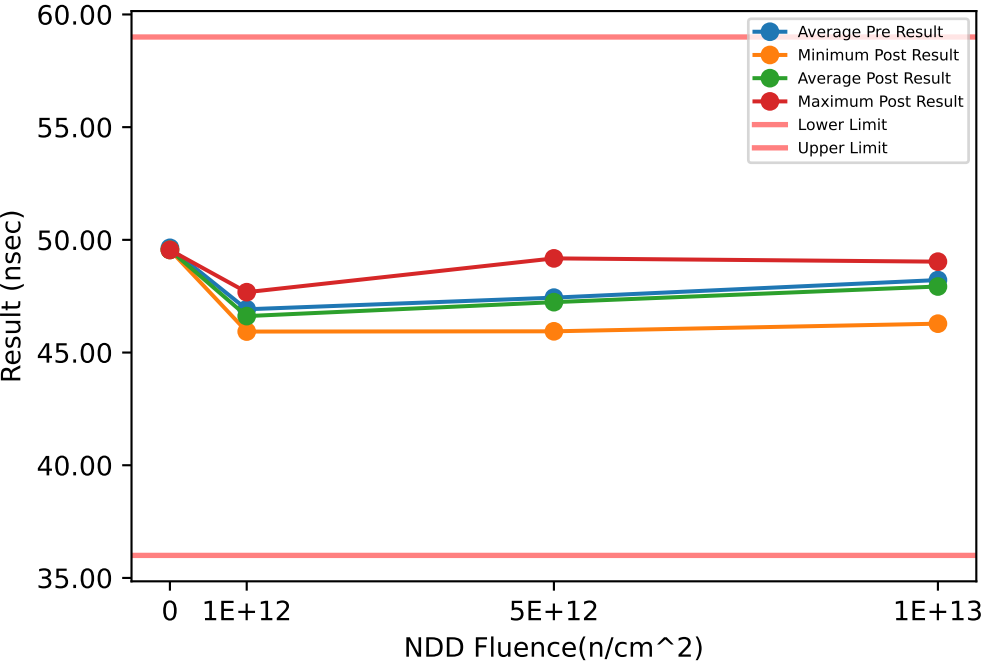


Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	21.724	21.724	21.724		21.446	21.446	21.446		-0.2779	-0.2779	-0.2779	
1e+12	20.676	20.902	21.192	0.26383	20.452	20.689	20.96	0.25607	-0.2312	-0.21247	-0.1822	0.026458
5e+12	21.097	21.289	21.542	0.22846	20.858	21.11	21.371	0.25684	-0.2392	-0.1792	-0.128	0.05612
1e+13	21.068	21.475	21.759	0.36109	20.86	21.288	21.594	0.38209	-0.2087	-0.18717	-0.1641	0.02234

Device Test: 95.8 T_RLH_LARGE(DLH Dead Time Large 1MHz VIN_10V)

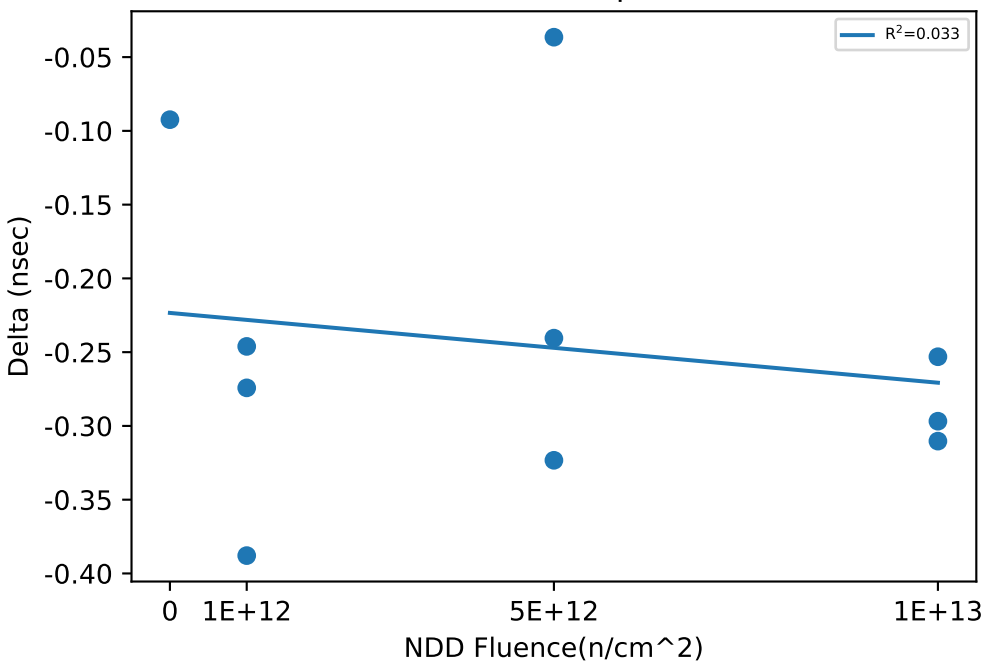
NDD vs Result Stats



Test Results (Lower Limit = 36.0, Upper Limit = 59.0 (nsec))

Serial #	Fluence(n/cm ²)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	46.488	46.242	-0.2461
551	1e+12	NDD	46.319	45.931	-0.3879
552	1e+12	NDD	47.952	47.678	-0.2742
553	5e+12	NDD	46.827	46.587	-0.2405
554	5e+12	NDD	46.265	45.942	-0.3233
555	5e+12	NDD	49.215	49.178	-0.0365
556	1e+13	NDD	46.534	46.281	-0.2531
557	1e+13	NDD	49.329	49.033	-0.2968
558	1e+13	NDD	48.786	48.475	-0.3103
559	0	NDD, Ctrl	49.646	49.553	-0.0924

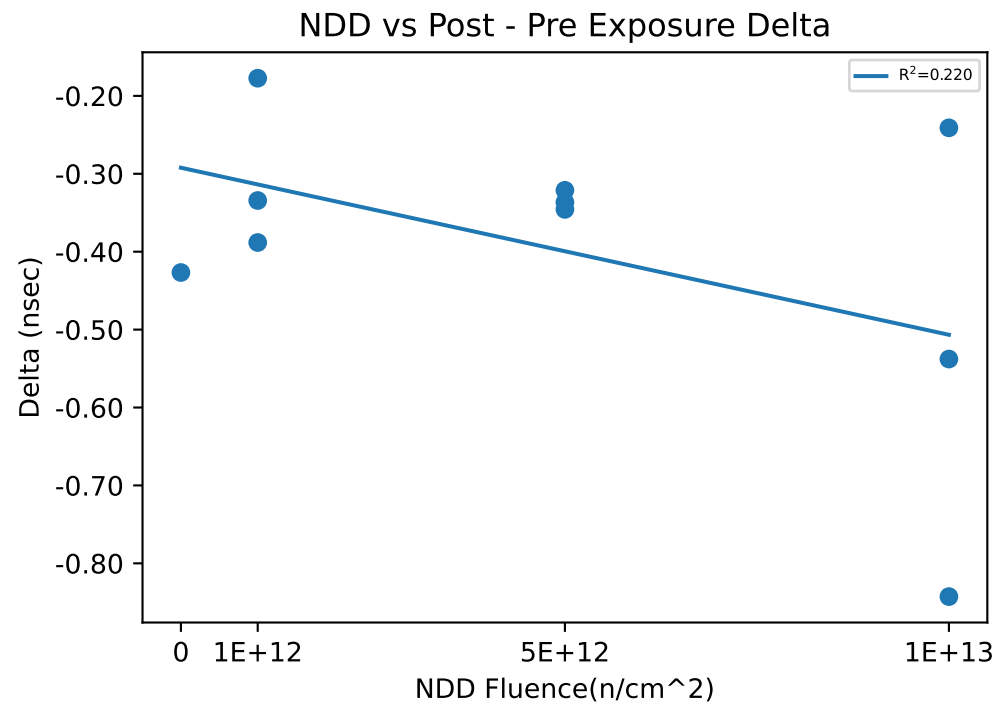
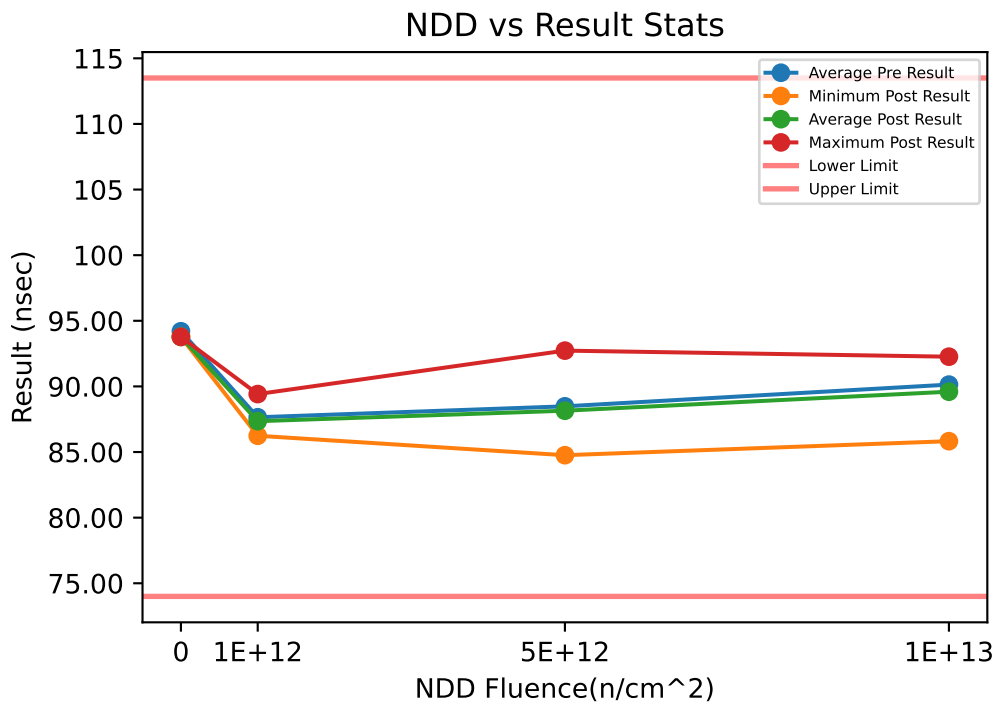
NDD vs Post - Pre Exposure Delta



Test Statistics (nsec)

Fluence(n/cm ²)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	49.646	49.646	49.646		49.553	49.553	49.553		-0.0924	-0.0924	-0.0924	
1e+12	46.319	46.92	47.952	0.89804	45.931	46.617	47.678	0.93181	-0.3879	-0.30273	-0.2461	0.075083
5e+12	46.265	47.436	49.215	1.5659	45.942	47.236	49.178	1.7128	-0.3233	-0.2001	-0.0365	0.14761
1e+13	46.534	48.216	49.329	1.4821	46.281	47.93	49.033	1.4548	-0.3103	-0.28673	-0.2531	0.029899

Device Test: 95.9 T_RLH_MAX(DLH Dead Time Max 1MHz VIN_10V)



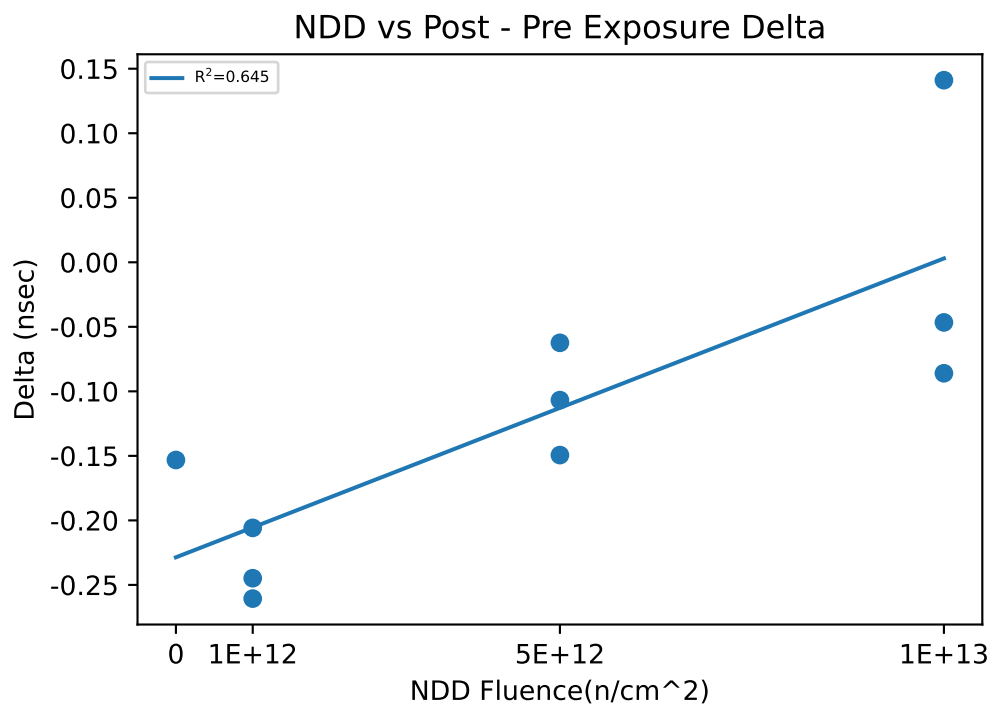
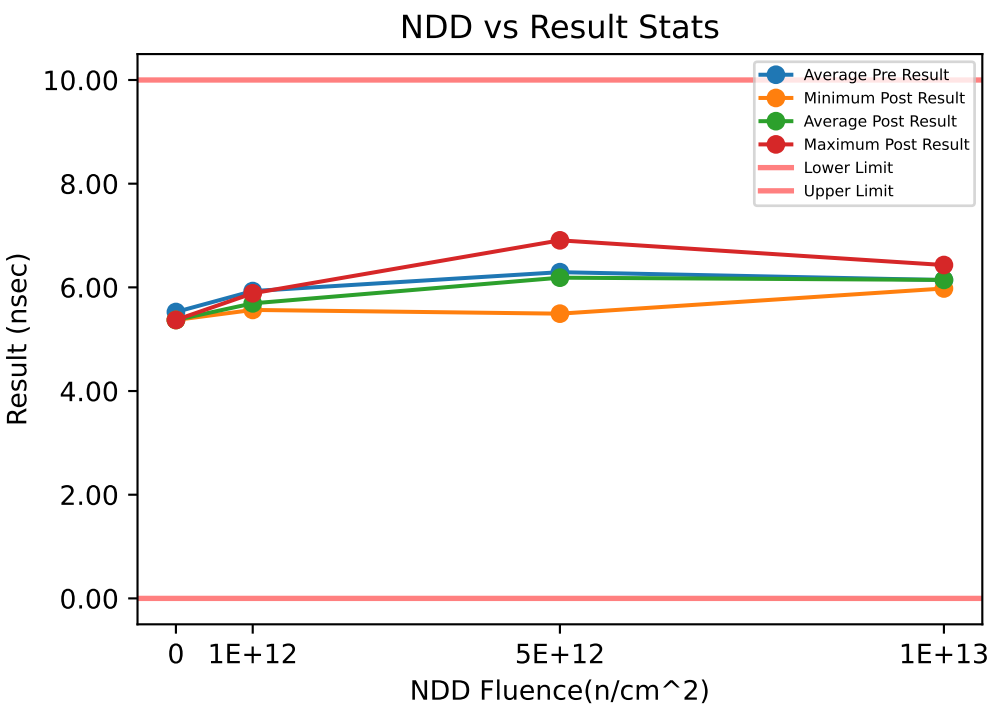
Test Results (Lower Limit = 74.0, Upper Limit = 113.5 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	86.567	86.39	-0.1773
551	1e+12	NDD	86.575	86.24	-0.3343
552	1e+12	NDD	89.804	89.416	-0.3882
553	5e+12	NDD	87.305	86.959	-0.3457
554	5e+12	NDD	85.08	84.759	-0.3212
555	5e+12	NDD	93.063	92.727	-0.3365
556	1e+13	NDD	86.068	85.827	-0.241
557	1e+13	NDD	92.803	92.265	-0.5378
558	1e+13	NDD	91.541	90.698	-0.8427
559	0	NDD, Ctrl	94.202	93.775	-0.4267

Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	94.202	94.202	94.202		93.775	93.775	93.775		-0.4267	-0.4267	-0.4267	
1e+12	86.567	87.649	89.804	1.8665	86.24	87.349	89.416	1.7916	-0.3882	-0.29993	-0.1773	0.10957
5e+12	85.08	88.483	93.063	4.12	84.759	88.148	92.727	4.115	-0.3457	-0.33447	-0.3212	0.012376
1e+13	86.068	90.137	92.803	3.5803	85.827	89.597	92.265	3.3576	-0.8427	-0.5405	-0.241	0.30086

Device Test: 96.0 T_RLH_MIN(DLH Dead Time Min 500kHz VIN_12V)



Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (nsec))

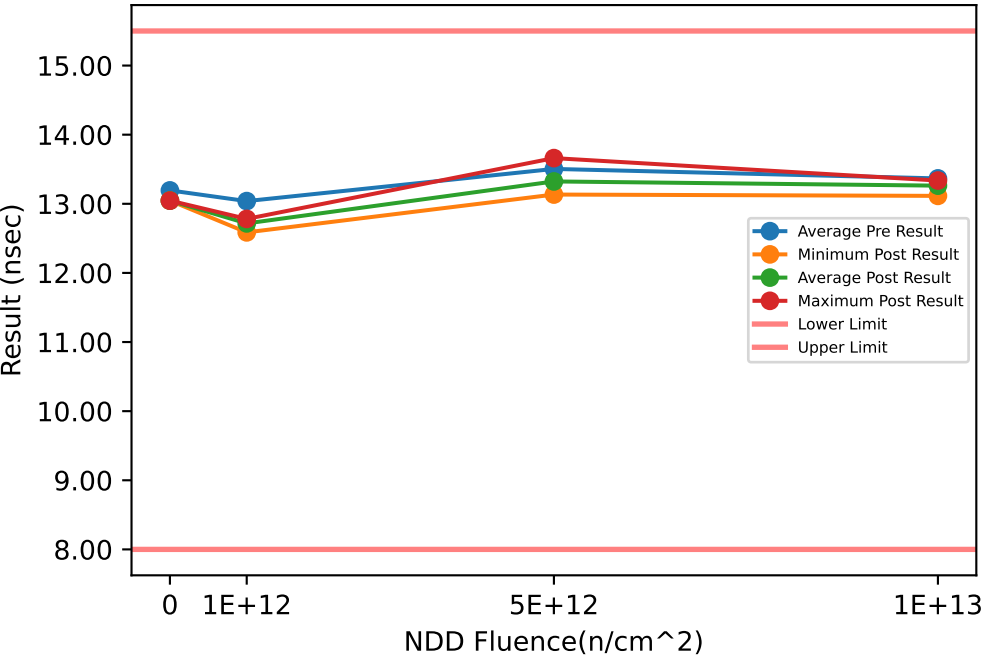
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	6.1459	5.8853	-0.2606
551	1e+12	NDD	5.8692	5.6244	-0.2448
552	1e+12	NDD	5.7704	5.5646	-0.2058
553	5e+12	NDD	6.2673	6.1605	-0.1068
554	5e+12	NDD	7.0564	6.907	-0.1494
555	5e+12	NDD	5.555	5.4926	-0.0624
556	1e+13	NDD	6.2898	6.4309	0.1411
557	1e+13	NDD	6.0643	5.9783	-0.086
558	1e+13	NDD	6.0687	6.0221	-0.0466
559	0	NDD, Ctrl	5.5245	5.3713	-0.1532

Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.5245	5.5245	5.5245		5.3713	5.3713	5.3713		-0.1532	-0.1532	-0.1532	
1e+12	5.7704	5.9285	6.1459	0.19465	5.5646	5.6914	5.8853	0.17054	-0.2606	-0.23707	-0.2058	0.028207
5e+12	5.555	6.2929	7.0564	0.75103	5.4926	6.1867	6.907	0.70756	-0.1494	-0.1062	-0.0624	0.043503
1e+13	6.0643	6.1409	6.2898	0.12894	5.9783	6.1438	6.4309	0.24963	-0.086	0.0028333	0.1411	0.12135

Device Test: 96.1 T_RLH_SMALL(DLH Dead Time Small 500kHz VIN_12V)

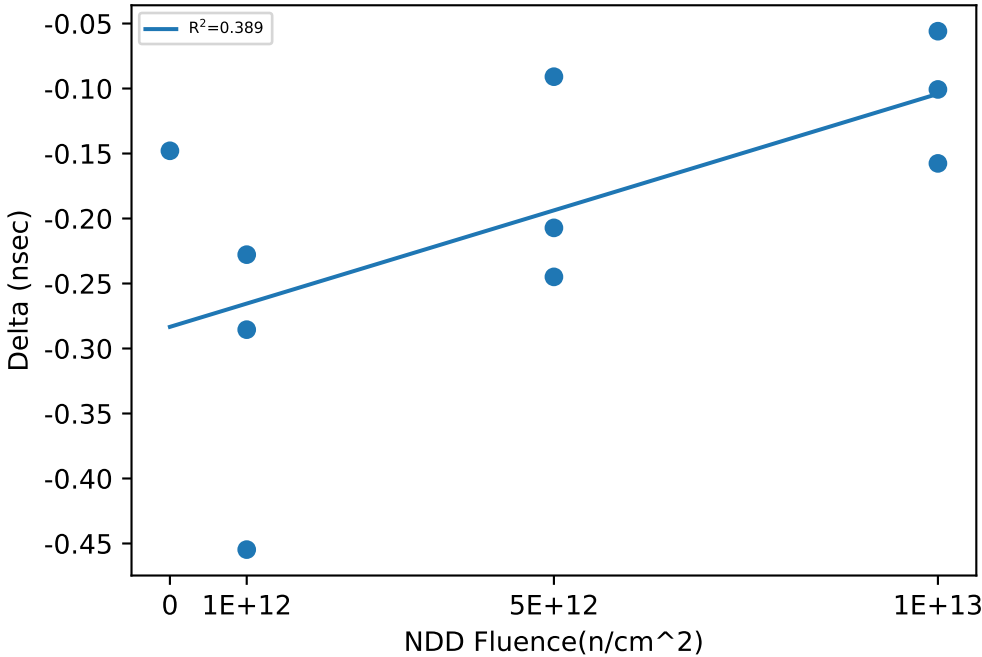
NDD vs Result Stats



Test Results (Lower Limit = 8.0, Upper Limit = 15.5 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	13.009	12.781	-0.2278
551	1e+12	NDD	12.872	12.587	-0.2855
552	1e+12	NDD	13.236	12.781	-0.4547
553	5e+12	NDD	13.421	13.176	-0.2449
554	5e+12	NDD	13.868	13.661	-0.2072
555	5e+12	NDD	13.225	13.134	-0.0909
556	1e+13	NDD	13.272	13.115	-0.1576
557	1e+13	NDD	13.437	13.337	-0.1007
558	1e+13	NDD	13.393	13.337	-0.0559
559	0	NDD, Ctrl	13.194	13.046	-0.1479

NDD vs Post - Pre Exposure Delta

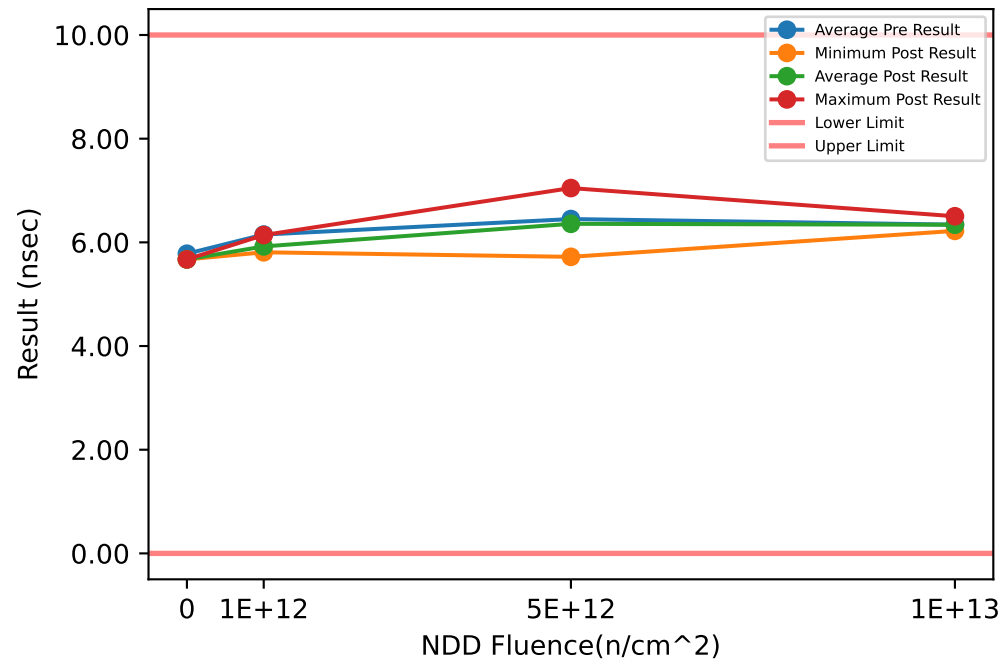


Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	13.194	13.194	13.194		13.046	13.046	13.046		-0.1479	-0.1479	-0.1479	
1e+12	12.872	13.039	13.236	0.18391	12.587	12.716	12.781	0.11241	-0.4547	-0.32267	-0.2278	0.11793
5e+12	13.225	13.505	13.868	0.32984	13.134	13.324	13.661	0.29301	-0.2449	-0.181	-0.0909	0.080273
1e+13	13.272	13.367	13.437	0.085323	13.115	13.263	13.337	0.12811	-0.1576	-0.10473	-0.0559	0.05097

Device Test: 96.10 T_RLH_MIN(DLH Dead Time Min 2MHz VIN_12V)

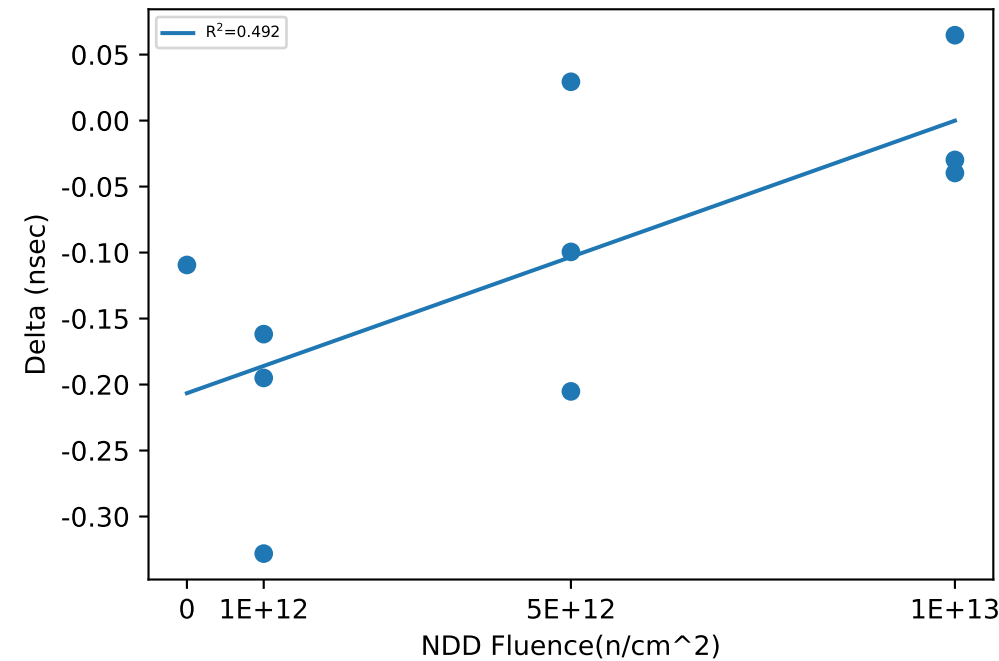
NDD vs Result Stats



Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	6.3027	6.1409	-0.1618
551	1e+12	NDD	6.1435	5.8154	-0.3281
552	1e+12	NDD	6.0033	5.8083	-0.195
553	5e+12	NDD	6.4048	6.3053	-0.0995
554	5e+12	NDD	7.2527	7.0475	-0.2052
555	5e+12	NDD	5.6911	5.7205	0.0294
556	1e+13	NDD	6.5433	6.5036	-0.0397
557	1e+13	NDD	6.2511	6.2213	-0.0298
558	1e+13	NDD	6.2297	6.2944	0.0647
559	0	NDD, Ctrl	5.7808	5.6714	-0.1094

NDD vs Post - Pre Exposure Delta

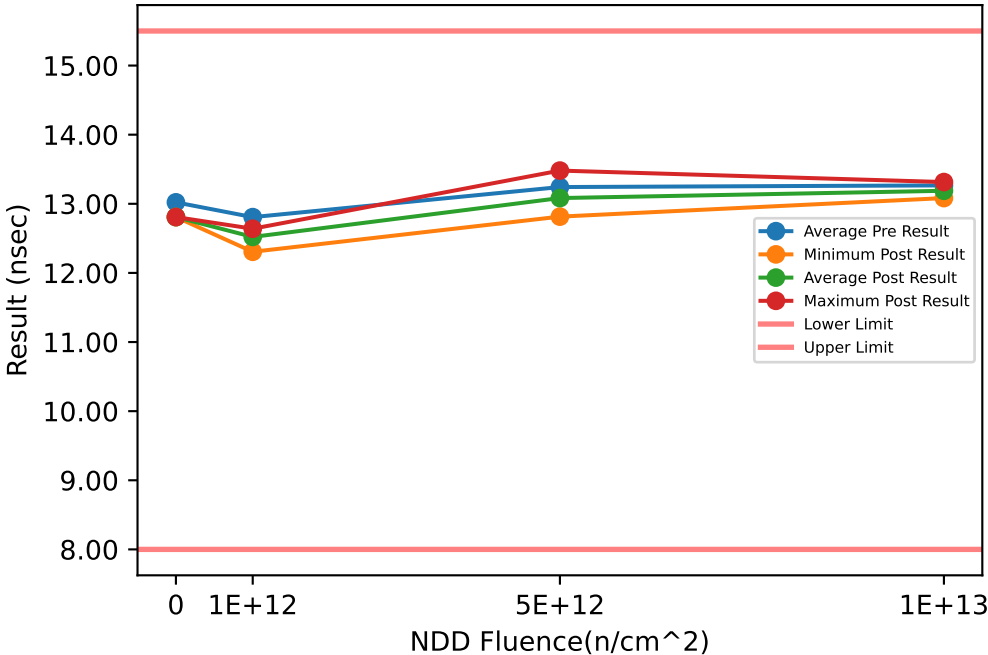


Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.7808	5.7808	5.7808		5.6714	5.6714	5.6714		-0.1094	-0.1094	-0.1094	
1e+12	6.0033	6.1498	6.3027	0.1498	5.8083	5.9215	6.1409	0.19001	-0.3281	-0.2283	-0.1618	0.088009
5e+12	5.6911	6.4495	7.2527	0.78176	5.7205	6.3578	7.0475	0.66505	-0.2052	-0.091767	0.0294	0.11749
1e+13	6.2297	6.3414	6.5433	0.17521	6.2213	6.3398	6.5036	0.14652	-0.0397	-0.0016	0.0647	0.05763

Device Test: 96.11 T_RLH_SMALL(DLH Dead Time Small 2MHz VIN_12V)

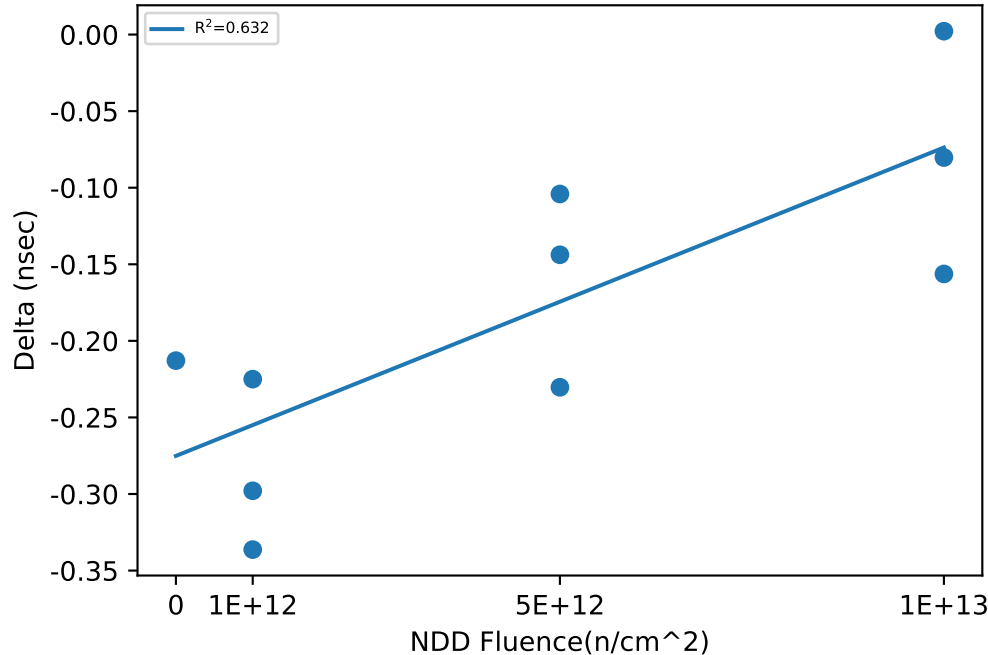
NDD vs Result Stats



Test Results (Lower Limit = 8.0, Upper Limit = 15.5 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	12.842	12.617	-0.225
551	1e+12	NDD	12.604	12.306	-0.2979
552	1e+12	NDD	12.976	12.639	-0.3363
553	5e+12	NDD	13.058	12.954	-0.1041
554	5e+12	NDD	13.711	13.48	-0.2303
555	5e+12	NDD	12.958	12.814	-0.1438
556	1e+13	NDD	13.239	13.083	-0.1563
557	1e+13	NDD	13.395	13.315	-0.0803
558	1e+13	NDD	13.165	13.167	0.0022
559	0	NDD, Ctrl	13.021	12.808	-0.2129

NDD vs Post - Pre Exposure Delta

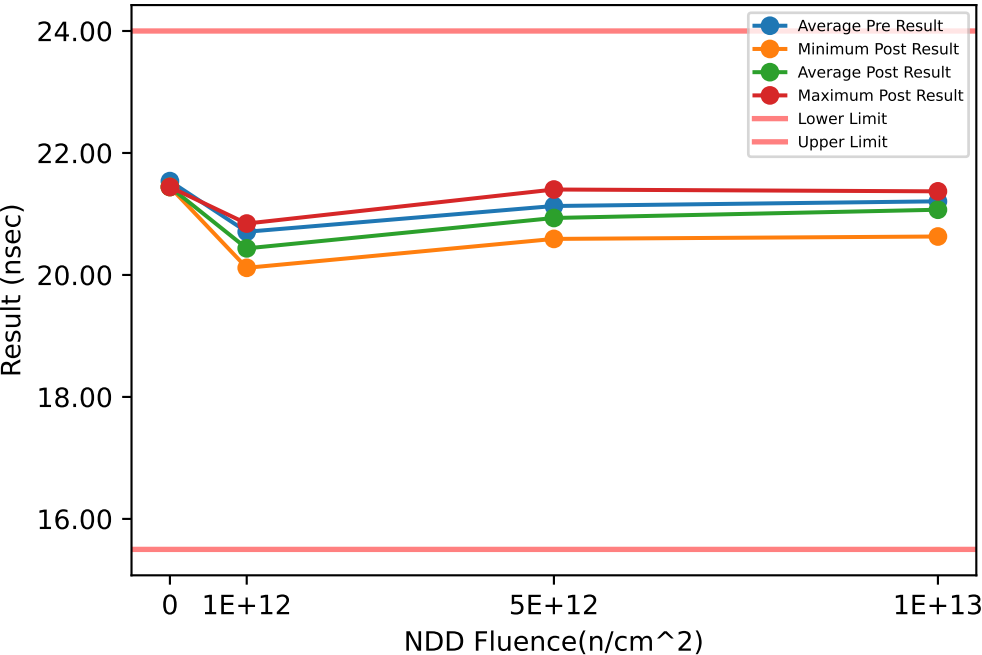


Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	13.021	13.021	13.021		12.808	12.808	12.808		-0.2129	-0.2129	-0.2129	
1e+12	12.604	12.807	12.976	0.18835	12.306	12.521	12.639	0.18641	-0.3363	-0.2864	-0.225	0.056534
5e+12	12.958	13.242	13.711	0.40874	12.814	13.083	13.48	0.35128	-0.2303	-0.1594	-0.1041	0.06453
1e+13	13.165	13.266	13.395	0.11736	13.083	13.188	13.315	0.11736	-0.1563	-0.078133	0.0022	0.079272

Device Test: 96.12 T_RLH_MID(DLH Dead Time Mid 2MHz VIN_12V)

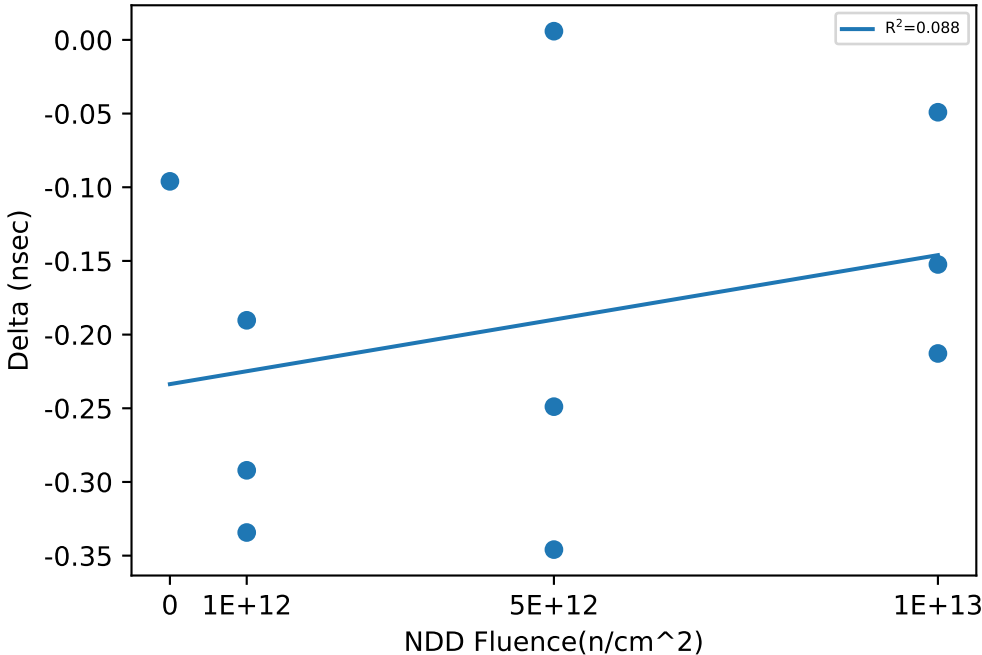
NDD vs Result Stats



Test Results (Lower Limit = 15.5, Upper Limit = 24.0 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	20.64	20.348	-0.2921
551	1e+12	NDD	20.451	20.117	-0.3343
552	1e+12	NDD	21.033	20.843	-0.1903
553	5e+12	NDD	20.84	20.591	-0.2489
554	5e+12	NDD	21.156	20.81	-0.3459
555	5e+12	NDD	21.395	21.401	0.0059
556	1e+13	NDD	20.679	20.63	-0.0491
557	1e+13	NDD	21.523	21.371	-0.1524
558	1e+13	NDD	21.419	21.206	-0.2128
559	0	NDD, Ctrl	21.539	21.443	-0.096

NDD vs Post - Pre Exposure Delta

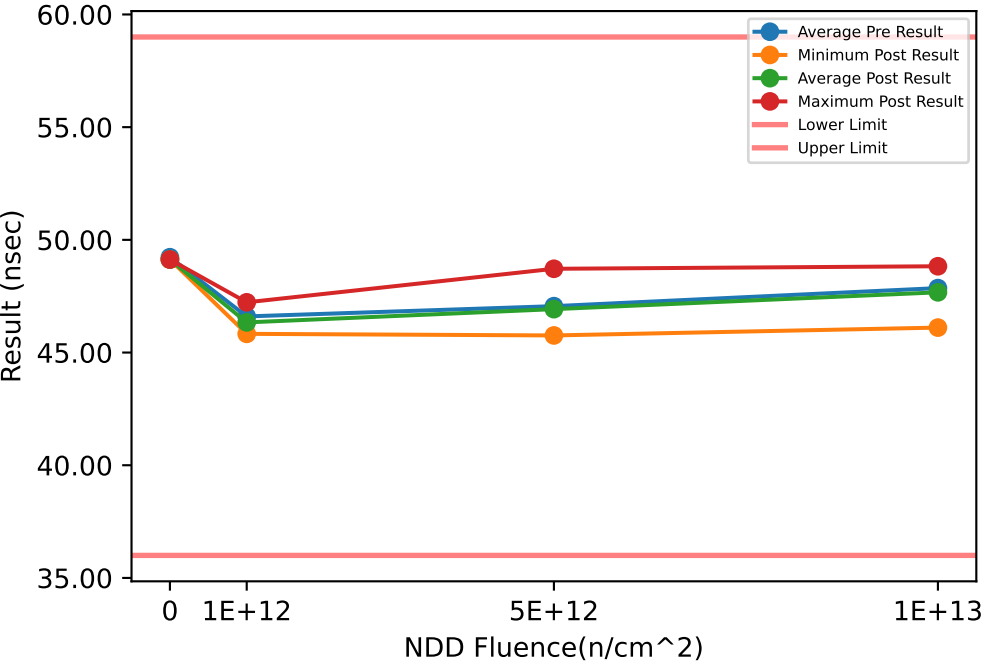


Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	21.539	21.539	21.539		21.443	21.443	21.443		-0.096	-0.096	-0.096	
1e+12	20.451	20.708	21.033	0.29693	20.117	20.436	20.843	0.37093	-0.3343	-0.27223	-0.1903	0.074027
5e+12	20.84	21.13	21.395	0.27845	20.591	20.934	21.401	0.41888	-0.3459	-0.1963	0.0059	0.1817
1e+13	20.679	21.207	21.523	0.46019	20.63	21.069	21.371	0.38895	-0.2128	-0.1381	-0.0491	0.082782

Device Test: 96.13 T_RLH_LARGE(DLH Dead Time Large 2MHz VIN_12V)

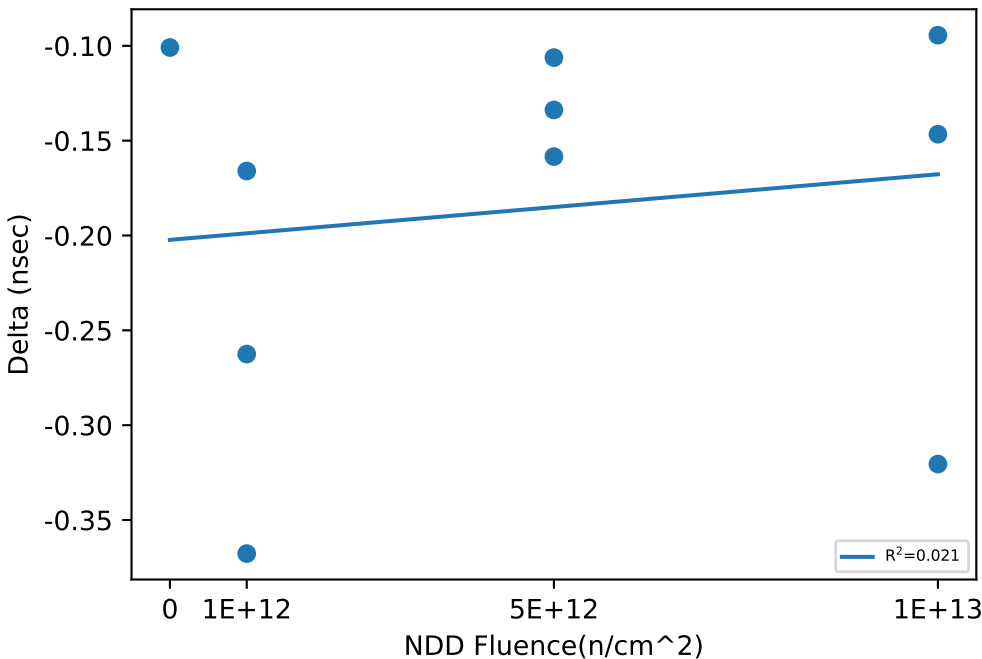
NDD vs Result Stats



Test Results (Lower Limit = 36.0, Upper Limit = 59.0 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	46.216	45.954	-0.2625
551	1e+12	NDD	45.996	45.83	-0.166
552	1e+12	NDD	47.596	47.228	-0.3677
553	5e+12	NDD	46.435	46.301	-0.1338
554	5e+12	NDD	45.865	45.759	-0.1062
555	5e+12	NDD	48.875	48.716	-0.1584
556	1e+13	NDD	46.253	46.107	-0.1466
557	1e+13	NDD	48.923	48.828	-0.0944
558	1e+13	NDD	48.402	48.081	-0.3205
559	0	NDD, Ctrl	49.229	49.128	-0.1009

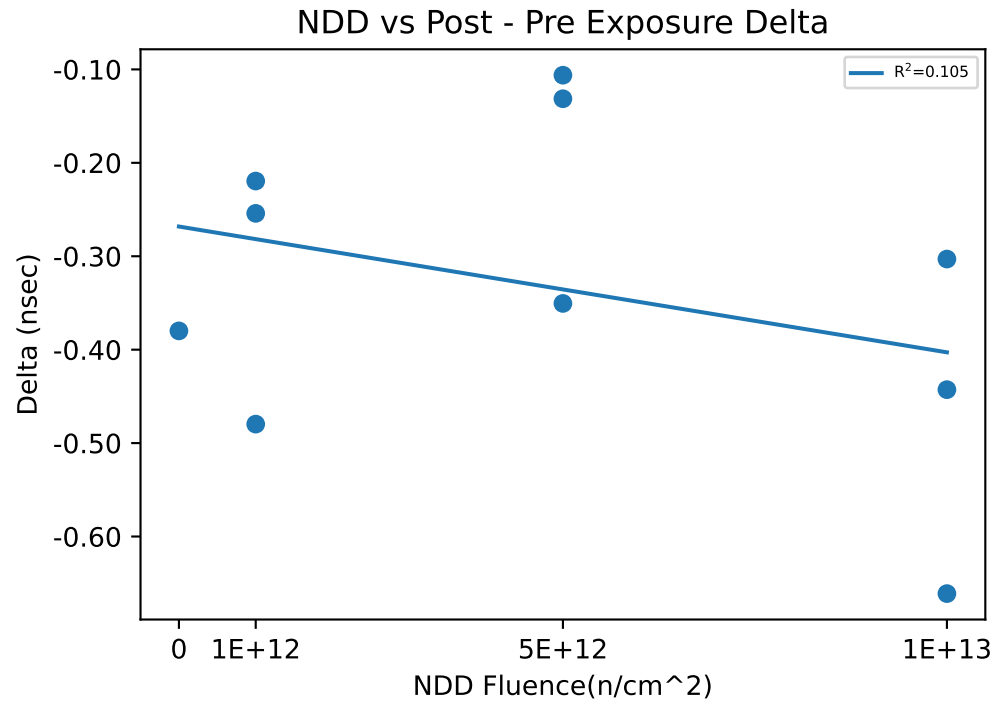
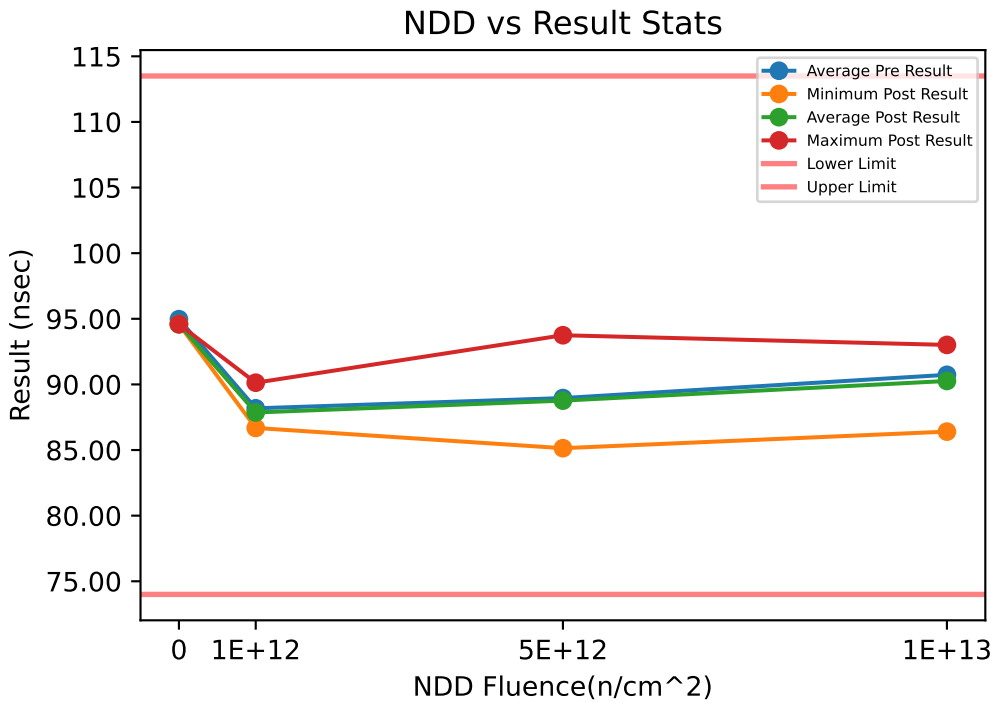
NDD vs Post - Pre Exposure Delta



Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	49.229	49.229	49.229		49.128	49.128	49.128		-0.1009	-0.1009	-0.1009	
1e+12	45.996	46.603	47.596	0.86734	45.83	46.337	47.228	0.7742	-0.3677	-0.2654	-0.166	0.10088
5e+12	45.865	47.058	48.875	1.5987	45.759	46.925	48.716	1.5745	-0.1584	-0.1328	-0.1062	0.026114
1e+13	46.253	47.859	48.923	1.4149	46.107	47.672	48.828	1.4061	-0.3205	-0.18717	-0.0944	0.11838

Device Test: 96.14 T_RLH_MAX(DLH Dead Time Max 2MHz VIN_12V)



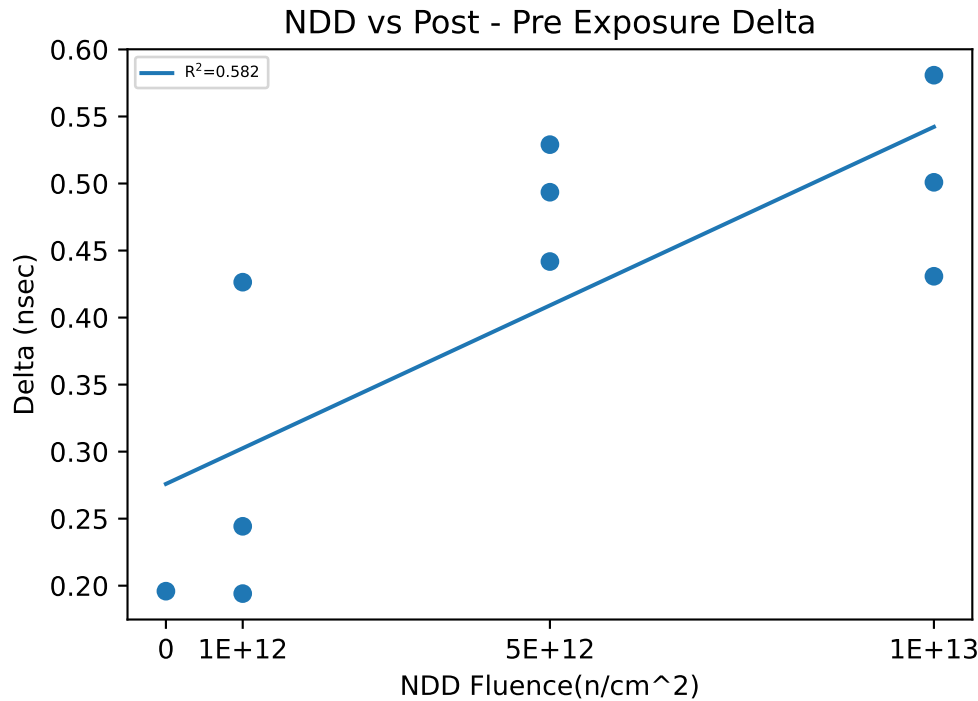
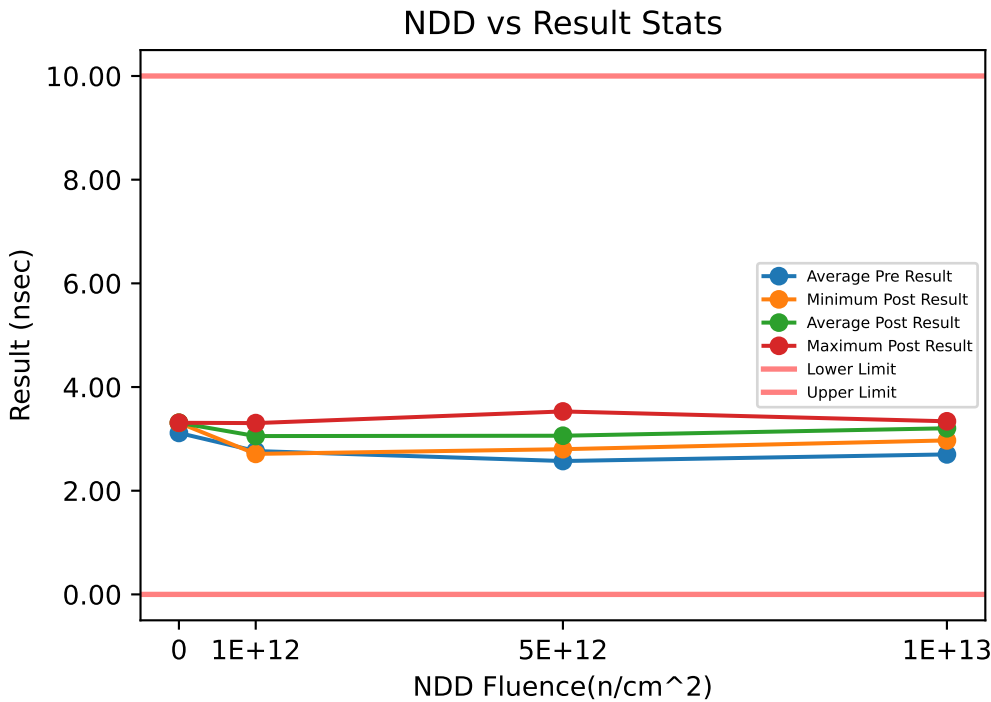
Test Results (Lower Limit = 74.0,
Upper Limit = 113.5 (nsec))

Serial #	Fluence(n/cm ²)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	87.022	86.767	-0.2541
551	1e+12	NDD	87.163	86.683	-0.4797
552	1e+12	NDD	90.35	90.131	-0.2195
553	5e+12	NDD	87.537	87.405	-0.1314
554	5e+12	NDD	85.491	85.141	-0.3505
555	5e+12	NDD	93.853	93.746	-0.1062
556	1e+13	NDD	86.706	86.403	-0.303
557	1e+13	NDD	93.454	93.011	-0.4428
558	1e+13	NDD	92.034	91.373	-0.6611
559	0	NDD, Ctrl	94.971	94.591	-0.3799

Test Statistics (nsec)

Fluence(n/cm ²)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	94.971	94.971	94.971		94.591	94.591	94.591		-0.3799	-0.3799	-0.3799	
1e+12	87.022	88.178	90.35	1.8823	86.683	87.861	90.131	1.9666	-0.4797	-0.31777	-0.2195	0.1413
5e+12	85.491	88.96	93.853	4.3586	85.141	88.764	93.746	4.4608	-0.3505	-0.19603	-0.1062	0.13436
1e+13	86.706	90.731	93.454	3.5575	86.403	90.262	93.011	3.4411	-0.6611	-0.46897	-0.303	0.18048

Device Test: 96.19 T_RHL_MIN(DHL Dead Time Min 500kHz VIN_12V)



Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (nsec))

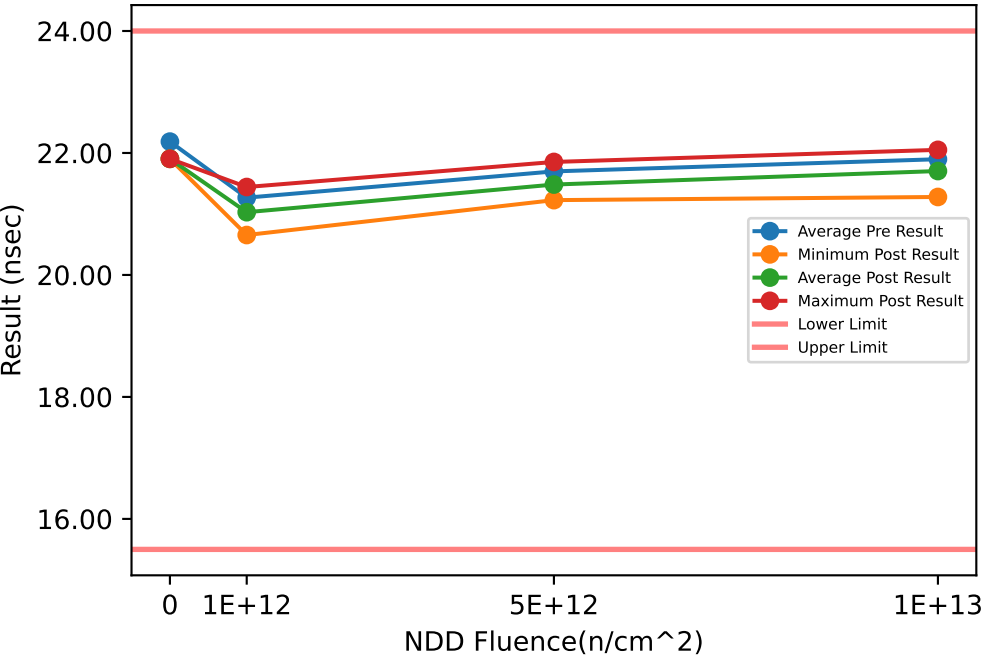
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	2.9036	3.1479	0.2443
551	1e+12	NDD	2.5162	2.7103	0.1941
552	1e+12	NDD	2.878	3.3044	0.4264
553	5e+12	NDD	3.0003	3.5293	0.529
554	5e+12	NDD	2.3074	2.8009	0.4935
555	5e+12	NDD	2.4102	2.852	0.4418
556	1e+13	NDD	2.5395	2.9703	0.4308
557	1e+13	NDD	2.7583	3.3391	0.5808
558	1e+13	NDD	2.8034	3.3043	0.5009
559	0	NDD, Ctrl	3.1145	3.3104	0.1959

Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.1145	3.1145	3.1145		3.3104	3.3104	3.3104		0.1959	0.1959	0.1959	
1e+12	2.5162	2.7659	2.9036	0.21665	2.7103	3.0542	3.3044	0.30793	0.1941	0.28827	0.4264	0.12223
5e+12	2.3074	2.5726	3.0003	0.37392	2.8009	3.0607	3.5293	0.40659	0.4418	0.4881	0.529	0.04385
1e+13	2.5395	2.7004	2.8034	0.14116	2.9703	3.2046	3.3391	0.20363	0.4308	0.50417	0.5808	0.075053

Device Test: 96.2 T_RLH_MID(DLH Dead Time Mid 500kHz VIN_12V)

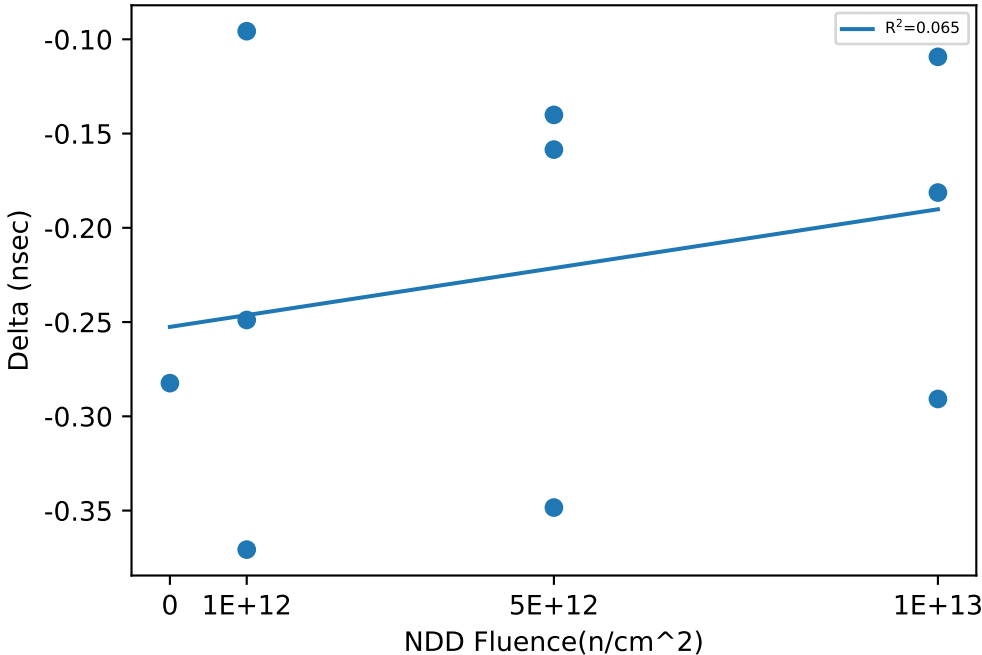
NDD vs Result Stats



Test Results (Lower Limit = 15.5, Upper Limit = 24.0 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	21.239	20.991	-0.2489
551	1e+12	NDD	21.025	20.654	-0.3707
552	1e+12	NDD	21.538	21.442	-0.0957
553	5e+12	NDD	21.385	21.227	-0.1585
554	5e+12	NDD	21.716	21.367	-0.3484
555	5e+12	NDD	21.993	21.853	-0.1401
556	1e+13	NDD	21.388	21.279	-0.1093
557	1e+13	NDD	22.232	22.051	-0.1813
558	1e+13	NDD	22.073	21.782	-0.2908
559	0	NDD, Ctrl	22.186	21.904	-0.2824

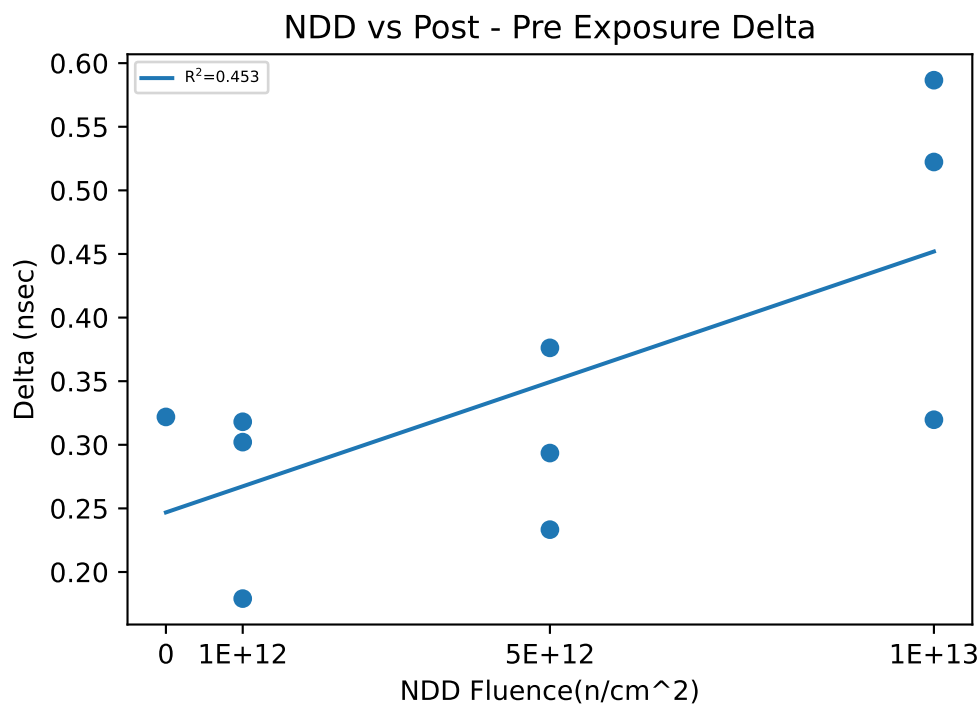
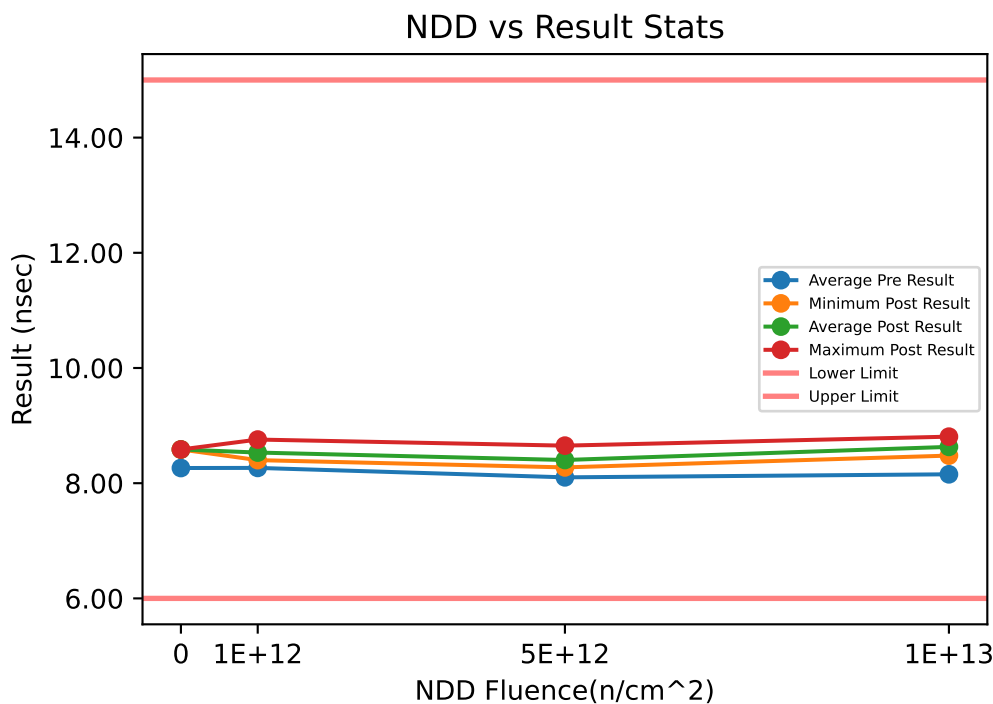
NDD vs Post - Pre Exposure Delta



Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	22.186	22.186	22.186		21.904	21.904	21.904		-0.2824	-0.2824	-0.2824	
1e+12	21.025	21.267	21.538	0.25729	20.654	21.029	21.442	0.39505	-0.3707	-0.23843	-0.0957	0.1378
5e+12	21.385	21.698	21.993	0.30419	21.227	21.482	21.853	0.32846	-0.3484	-0.21567	-0.1401	0.11532
1e+13	21.388	21.898	22.232	0.44867	21.279	21.704	22.051	0.39216	-0.2908	-0.1938	-0.1093	0.091393

Device Test: 96.20 T_RHL_SMALL(DHL Dead Time Small 500kHz VIN_12V)



Test Results (Lower Limit = 6.0,
Upper Limit = 15.0 (nsec))

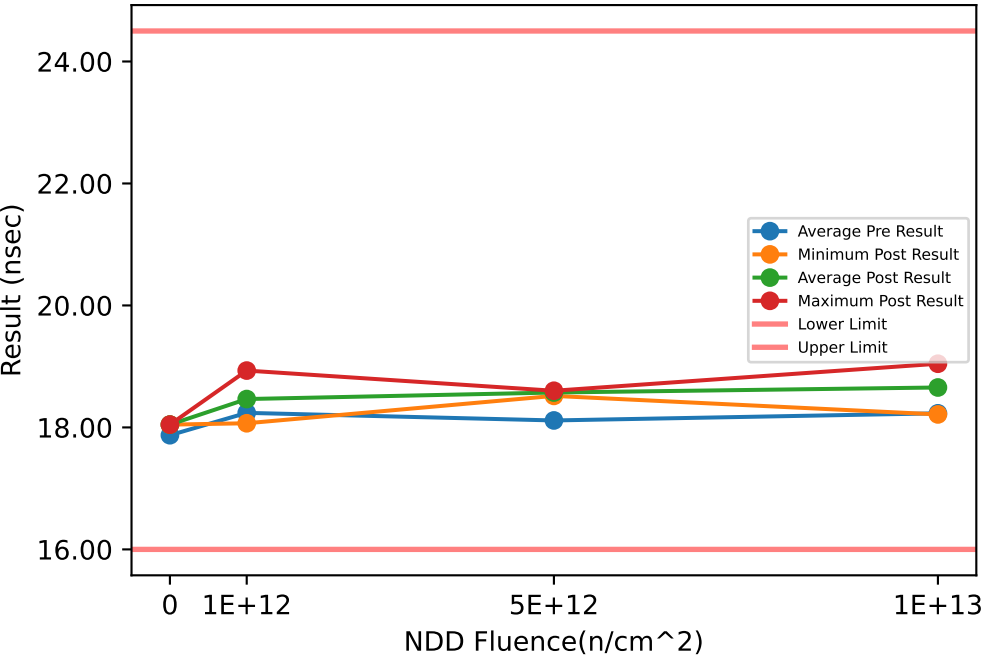
Serial #	Fluence(n/cm ²)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	8.2586	8.4377	0.1791
551	1e+12	NDD	8.0824	8.4005	0.3181
552	1e+12	NDD	8.4556	8.7577	0.3021
553	5e+12	NDD	8.4188	8.6521	0.2333
554	5e+12	NDD	7.9055	8.2817	0.3762
555	5e+12	NDD	7.9808	8.2743	0.2935
556	1e+13	NDD	8.1594	8.4791	0.3197
557	1e+13	NDD	8.2855	8.8078	0.5223
558	1e+13	NDD	8.0183	8.6049	0.5866
559	0	NDD, Ctrl	8.2636	8.5855	0.3219

Test Statistics (nsec)

Fluence(n/cm ²)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.2636	8.2636	8.2636		8.5855	8.5855	8.5855		0.3219	0.3219	0.3219	
1e+12	8.0824	8.2655	8.4556	0.1867	8.4005	8.532	8.7577	0.19637	0.1791	0.26643	0.3181	0.076055
5e+12	7.9055	8.1017	8.4188	0.27719	8.2743	8.4027	8.6521	0.21602	0.2333	0.301	0.3762	0.071745
1e+13	8.0183	8.1544	8.2855	0.13367	8.4791	8.6306	8.8078	0.16585	0.3197	0.4762	0.5866	0.13929

Device Test: 96.21 T_RHL_MID(DHL Dead Time Mid 500kHz VIN_12V)

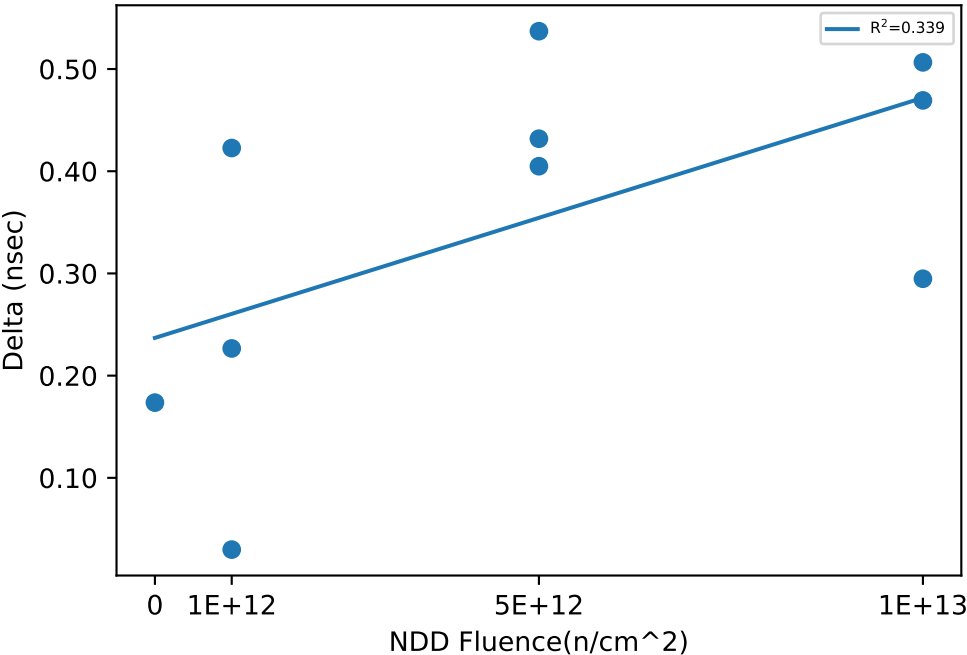
NDD vs Result Stats



Test Results (Lower Limit = 16.0, Upper Limit = 24.5 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	17.842	18.068	0.2266
551	1e+12	NDD	18.366	18.395	0.0298
552	1e+12	NDD	18.509	18.932	0.4227
553	5e+12	NDD	18.194	18.599	0.4049
554	5e+12	NDD	18.064	18.601	0.537
555	5e+12	NDD	18.085	18.517	0.4318
556	1e+13	NDD	18.412	18.707	0.2948
557	1e+13	NDD	18.575	19.044	0.4693
558	1e+13	NDD	17.707	18.213	0.5065
559	0	NDD, Ctrl	17.872	18.046	0.1736

NDD vs Post - Pre Exposure Delta

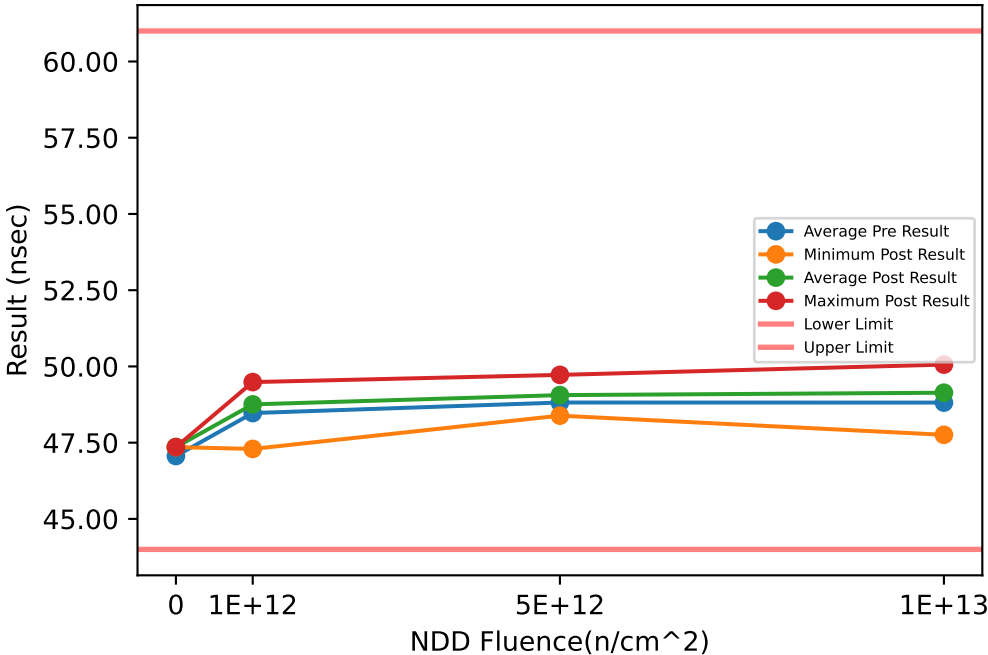


Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	17.872	17.872	17.872		18.046	18.046	18.046		0.1736	0.1736	0.1736	
1e+12	17.842	18.239	18.509	0.35148	18.068	18.465	18.932	0.43616	0.0298	0.22637	0.4227	0.19645
5e+12	18.064	18.114	18.194	0.069445	18.517	18.572	18.601	0.047853	0.4049	0.4579	0.537	0.069811
1e+13	17.707	18.231	18.575	0.46161	18.213	18.655	19.044	0.41805	0.2948	0.42353	0.5065	0.11303

Device Test: 96.22 T_RHL_LARGE(DHL Dead Time Large 500kHz VIN_12V)

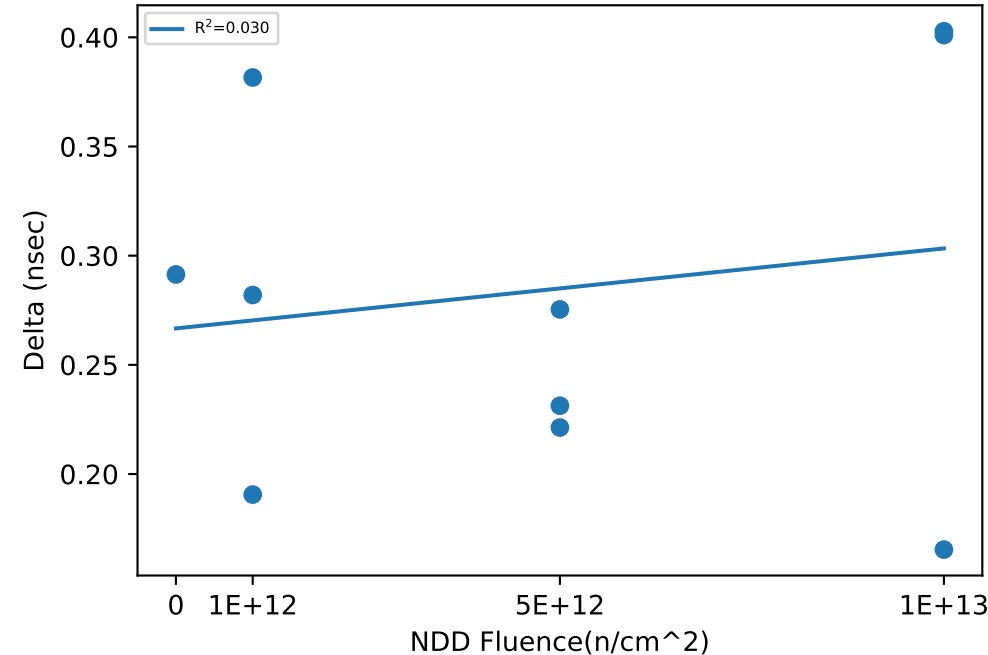
NDD vs Result Stats



Test Results (Lower Limit = 44.0, Upper Limit = 61.0 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	46.913	47.295	0.3816
551	1e+12	NDD	49.203	49.485	0.282
552	1e+12	NDD	49.296	49.487	0.1906
553	5e+12	NDD	48.111	48.386	0.2754
554	5e+12	NDD	49.501	49.722	0.2213
555	5e+12	NDD	48.839	49.07	0.2313
556	1e+13	NDD	49.429	49.595	0.1654
557	1e+13	NDD	49.657	50.06	0.4028
558	1e+13	NDD	47.357	47.758	0.401
559	0	NDD, Ctrl	47.062	47.353	0.2914

NDD vs Post - Pre Exposure Delta

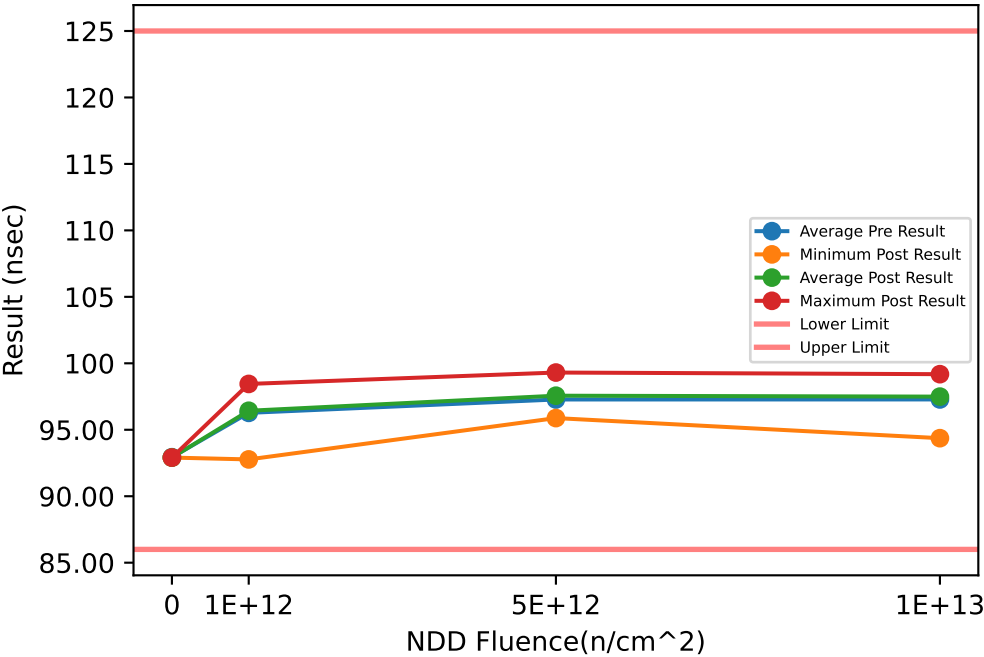


Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	47.062	47.062	47.062		47.353	47.353	47.353		0.2914	0.2914	0.2914	
1e+12	46.913	48.471	49.296	1.3497	47.295	48.756	49.487	1.265	0.1906	0.28473	0.3816	0.095529
5e+12	48.111	48.817	49.501	0.69561	48.386	49.059	49.722	0.66836	0.2213	0.24267	0.2754	0.028785
1e+13	47.357	48.814	49.657	1.2673	47.758	49.137	50.06	1.2171	0.1654	0.32307	0.4028	0.13655

Device Test: 96.23 T_RHL_MAX(DHL Dead Time Max 500kHz VIN_12V)

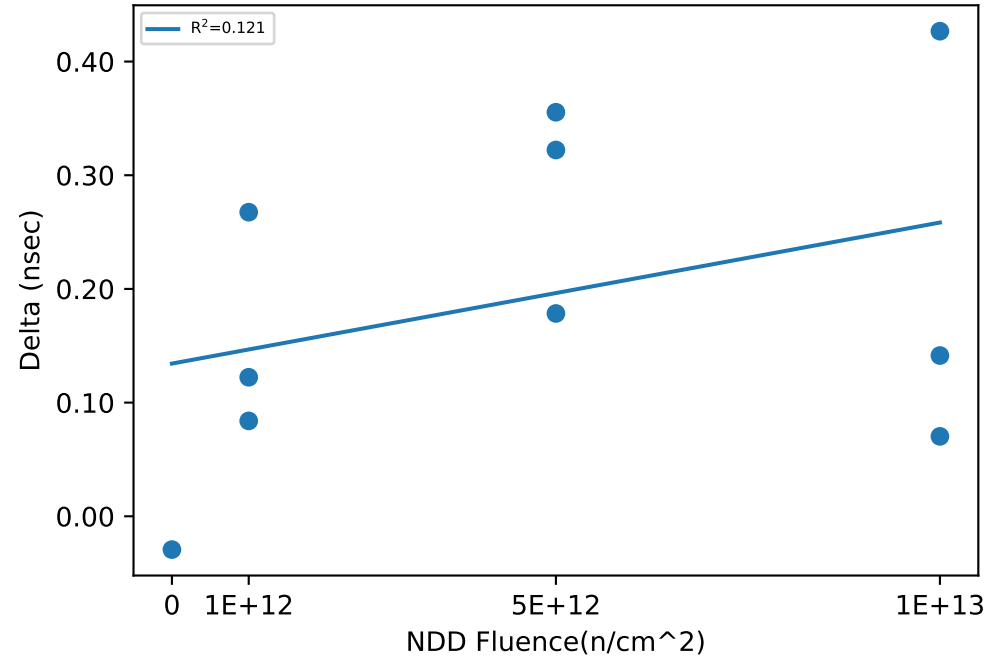
NDD vs Result Stats



Test Results (Lower Limit = 86.0, Upper Limit = 125.0 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	92.647	92.77	0.1223
551	1e+12	NDD	97.988	98.072	0.0839
552	1e+12	NDD	98.18	98.448	0.2675
553	5e+12	NDD	95.701	95.879	0.1784
554	5e+12	NDD	98.983	99.305	0.3222
555	5e+12	NDD	97.151	97.506	0.3554
556	1e+13	NDD	98.862	98.933	0.0703
557	1e+13	NDD	98.756	99.182	0.4267
558	1e+13	NDD	94.226	94.368	0.1414
559	0	NDD, Ctrl	92.937	92.907	-0.0293

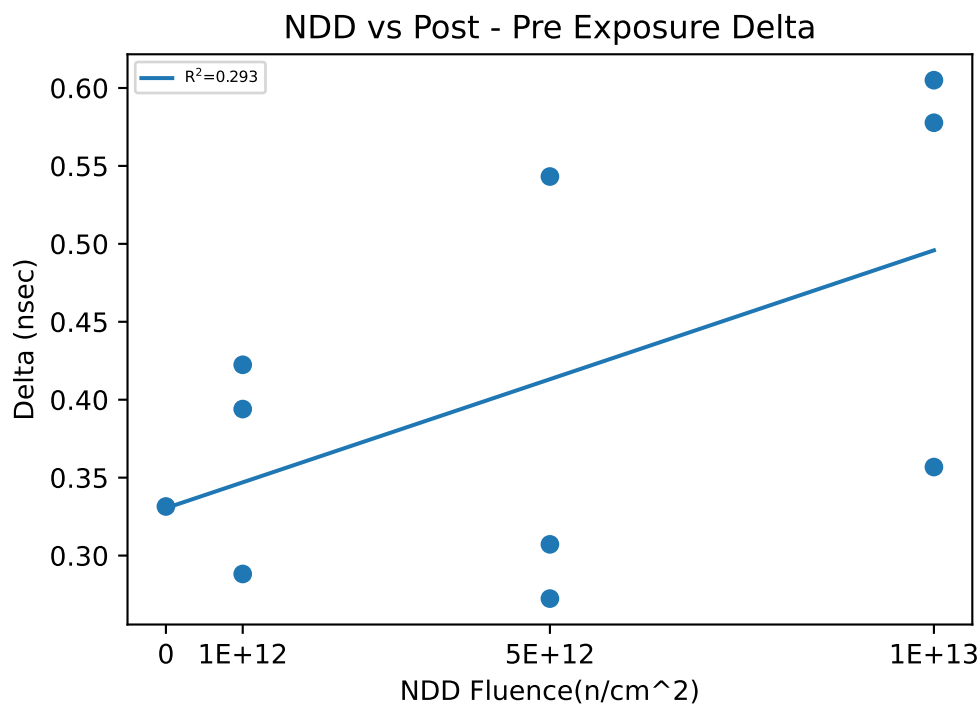
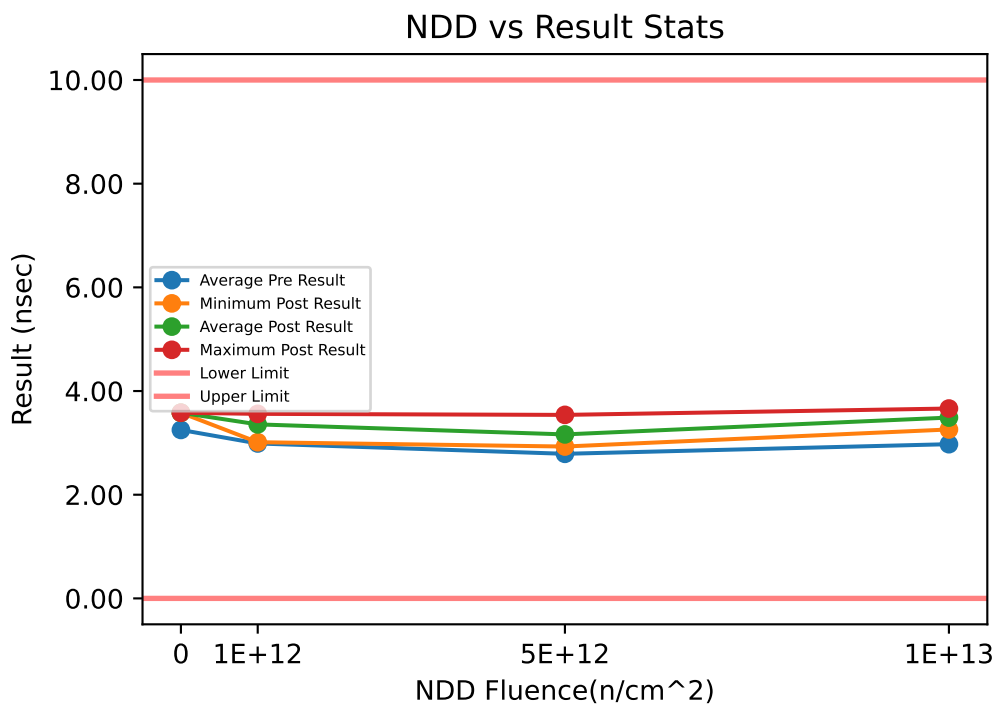
NDD vs Post - Pre Exposure Delta



Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	92.937	92.937	92.937		92.907	92.907	92.907		-0.0293	-0.0293	-0.0293	
1e+12	92.647	96.272	98.18	3.1405	92.77	96.43	98.448	3.1754	0.0839	0.1579	0.2675	0.096839
5e+12	95.701	97.278	98.983	1.6447	95.879	97.563	99.305	1.7136	0.1784	0.28533	0.3554	0.094083
1e+13	94.226	97.281	98.862	2.6465	94.368	97.494	99.182	2.7107	0.0703	0.2128	0.4267	0.18862

Device Test: 96.24 T_RHL_MIN(DHL Dead Time Min 1MHz VIN_12V)



Test Results (Lower Limit = 0.0,
Upper Limit = 10.0 (nsec))

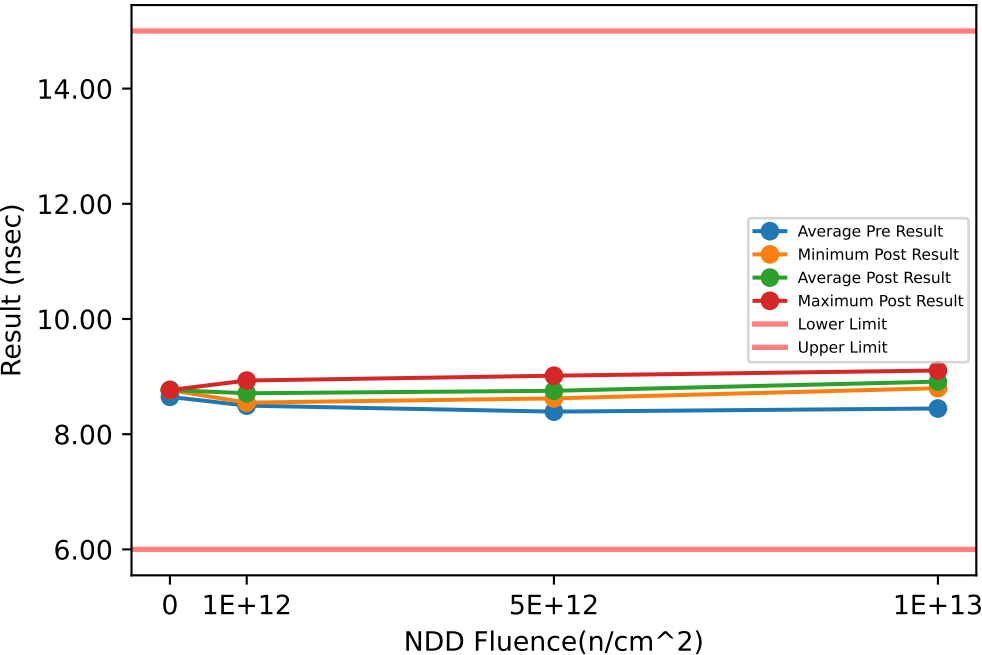
Serial #	Fluence(n/cm ²)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	3.1034	3.4974	0.394
551	1e+12	NDD	2.7248	3.013	0.2882
552	1e+12	NDD	3.1373	3.5597	0.4224
553	5e+12	NDD	3.2327	3.5399	0.3072
554	5e+12	NDD	2.4775	3.0207	0.5432
555	5e+12	NDD	2.6571	2.9295	0.2724
556	1e+13	NDD	2.9018	3.2586	0.3568
557	1e+13	NDD	2.9648	3.5425	0.5777
558	1e+13	NDD	3.0576	3.6626	0.605
559	0	NDD, Ctrl	3.2498	3.5813	0.3315

Test Statistics (nsec)

Fluence(n/cm ²)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.2498	3.2498	3.2498		3.5813	3.5813	3.5813		0.3315	0.3315	0.3315	
1e+12	2.7248	2.9885	3.1373	0.229	3.013	3.3567	3.5597	0.29928	0.2882	0.3682	0.4224	0.070722
5e+12	2.4775	2.7891	3.2327	0.39452	2.9295	3.1634	3.5399	0.32926	0.2724	0.37427	0.5432	0.14733
1e+13	2.9018	2.9747	3.0576	0.078374	3.2586	3.4879	3.6626	0.20746	0.3568	0.51317	0.605	0.1361

Device Test: 96.25 T_RHL_SMALL(DHL Dead Time Small 1MHz VIN_12V)

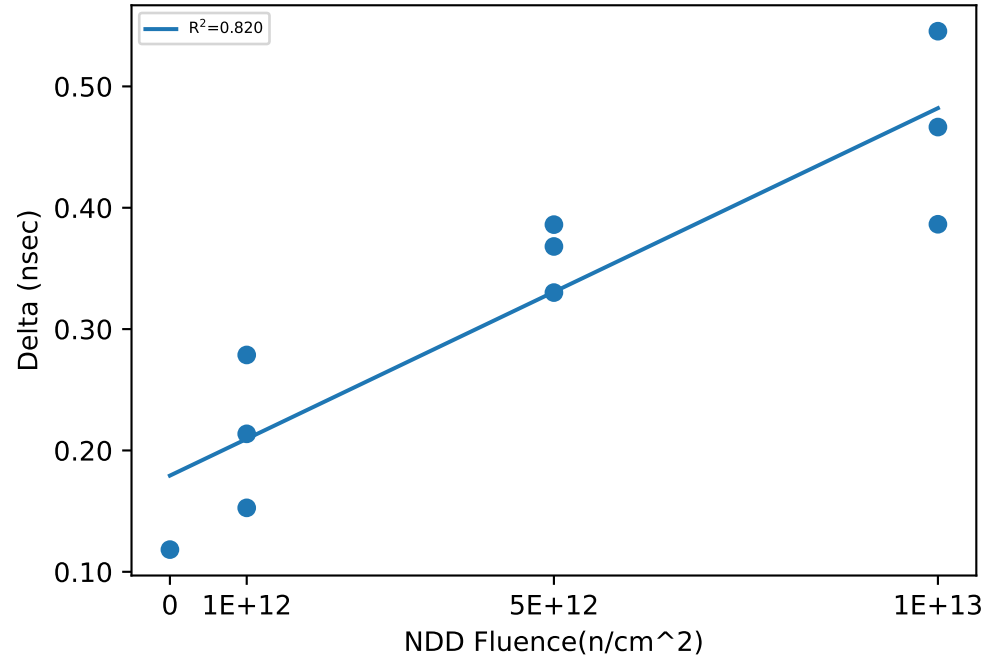
NDD vs Result Stats



Test Results (Lower Limit = 6.0, Upper Limit = 15.0 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	8.5005	8.6532	0.1527
551	1e+12	NDD	8.2692	8.5479	0.2787
552	1e+12	NDD	8.7179	8.9316	0.2137
553	5e+12	NDD	8.6853	9.0154	0.3301
554	5e+12	NDD	8.2545	8.6226	0.3681
555	5e+12	NDD	8.2355	8.6216	0.3861
556	1e+13	NDD	8.4122	8.7986	0.3864
557	1e+13	NDD	8.6392	9.1057	0.4665
558	1e+13	NDD	8.2873	8.8328	0.5455
559	0	NDD, Ctrl	8.6482	8.7665	0.1183

NDD vs Post - Pre Exposure Delta

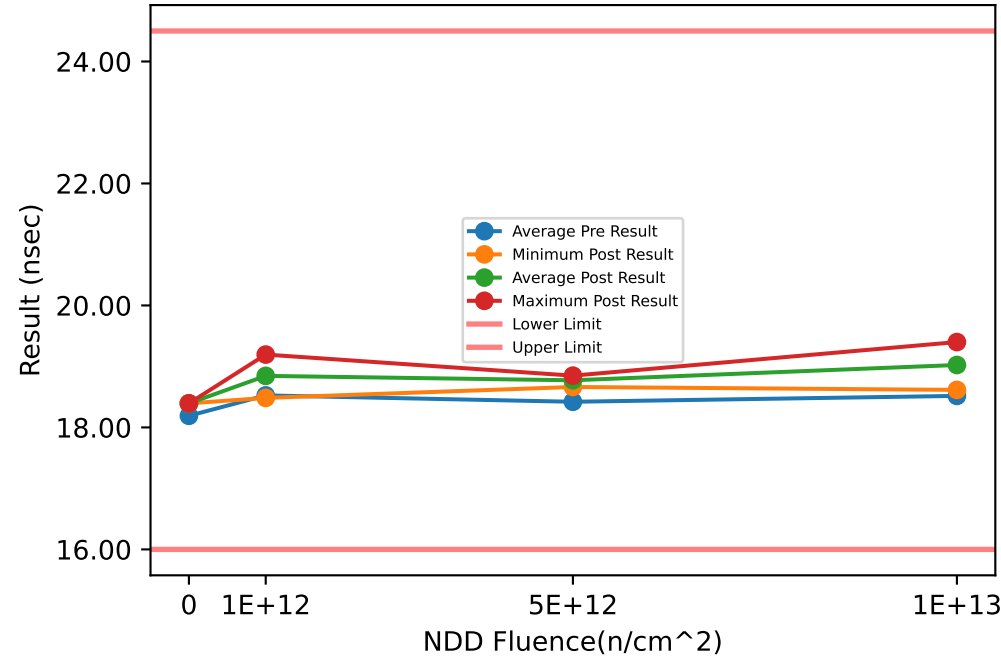


Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.6482	8.6482	8.6482		8.7665	8.7665	8.7665		0.1183	0.1183	0.1183	
1e+12	8.2692	8.4959	8.7179	0.22439	8.5479	8.7109	8.9316	0.19825	0.1527	0.21503	0.2787	0.063011
5e+12	8.2355	8.3918	8.6853	0.25438	8.6216	8.7532	9.0154	0.22707	0.3301	0.36143	0.3861	0.028589
1e+13	8.2873	8.4462	8.6392	0.1784	8.7986	8.9124	9.1057	0.1683	0.3864	0.46613	0.5455	0.079551

Device Test: 96.26 T_RHL_MID(DHL Dead Time Mid 1MHz VIN_12V)

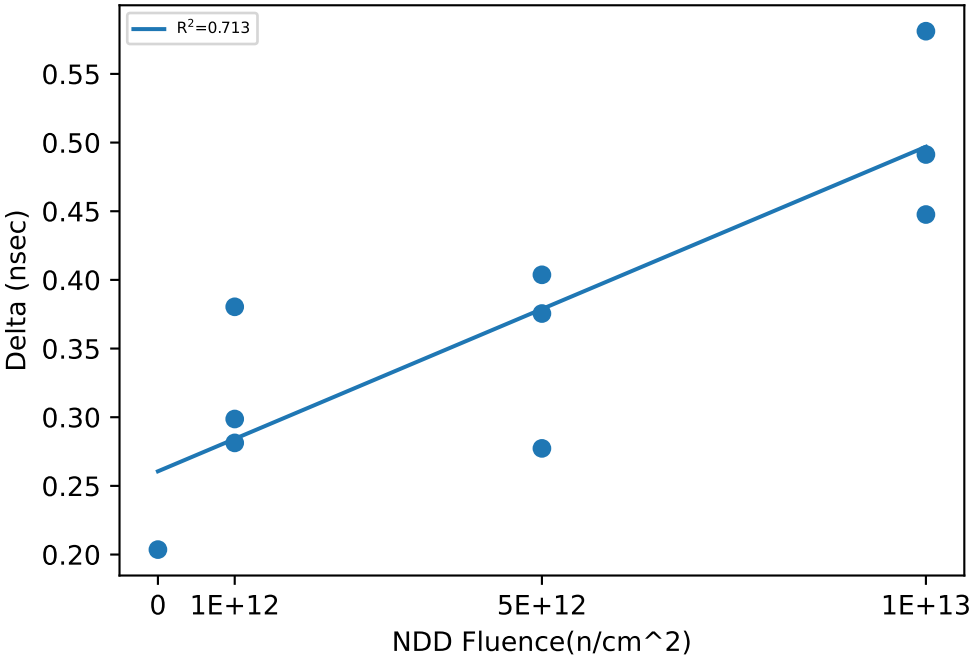
NDD vs Result Stats



Test Results (Lower Limit = 16.0, Upper Limit = 24.5 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	18.104	18.484	0.3804
551	1e+12	NDD	18.558	18.857	0.2987
552	1e+12	NDD	18.913	19.195	0.2813
553	5e+12	NDD	18.473	18.849	0.3755
554	5e+12	NDD	18.403	18.806	0.4037
555	5e+12	NDD	18.386	18.663	0.2773
556	1e+13	NDD	18.564	19.056	0.4913
557	1e+13	NDD	18.952	19.4	0.4476
558	1e+13	NDD	18.034	18.615	0.5811
559	0	NDD, Ctrl	18.191	18.394	0.2036

NDD vs Post - Pre Exposure Delta

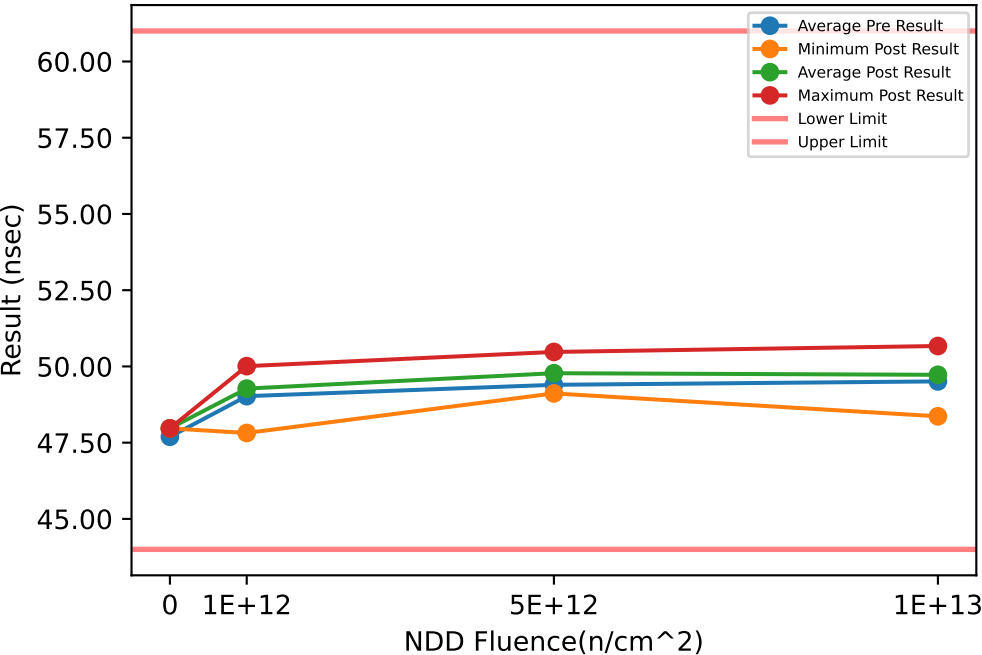


Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	18.191	18.191	18.191		18.394	18.394	18.394		0.2036	0.2036	0.2036	
1e+12	18.104	18.525	18.913	0.40583	18.484	18.845	19.195	0.3554	0.2813	0.32013	0.3804	0.052913
5e+12	18.386	18.421	18.473	0.046491	18.663	18.773	18.849	0.097333	0.2773	0.35217	0.4037	0.066352
1e+13	18.034	18.517	18.952	0.46079	18.615	19.024	19.4	0.39319	0.4476	0.50667	0.5811	0.068064

Device Test: 96.27 T_RHL_LARGE(DHL Dead Time Large 1MHz VIN_12V)

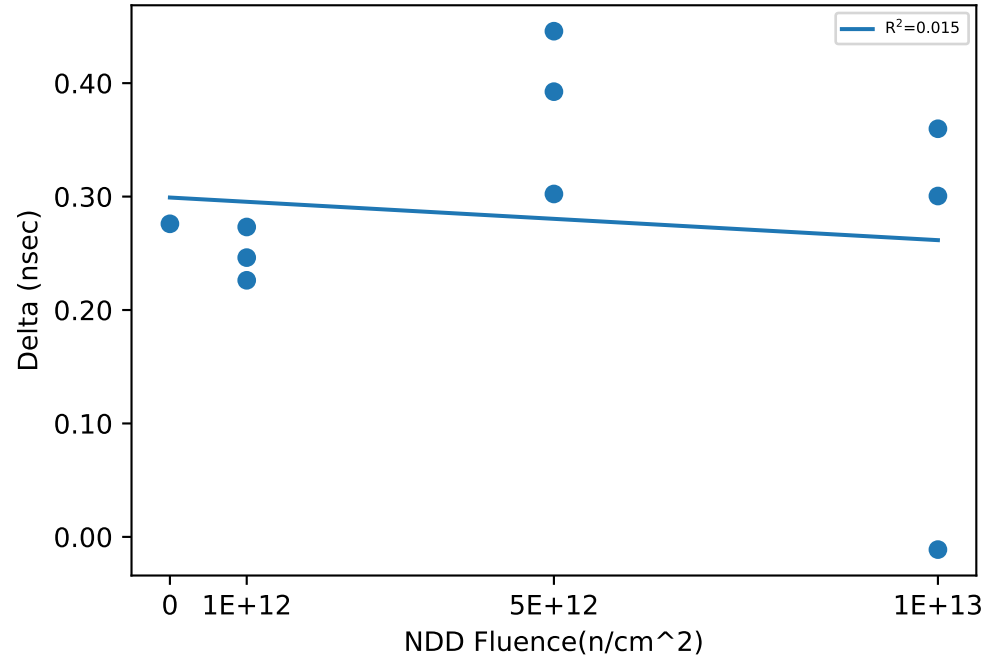
NDD vs Result Stats



Test Results (Lower Limit = 44.0, Upper Limit = 61.0 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	47.545	47.818	0.2732
551	1e+12	NDD	49.767	49.993	0.2262
552	1e+12	NDD	49.763	50.01	0.2462
553	5e+12	NDD	48.723	49.116	0.3925
554	5e+12	NDD	50.029	50.475	0.4458
555	5e+12	NDD	49.439	49.742	0.3023
556	1e+13	NDD	50.154	50.143	-0.0112
557	1e+13	NDD	50.369	50.67	0.3005
558	1e+13	NDD	48.005	48.365	0.3598
559	0	NDD, Ctrl	47.693	47.969	0.276

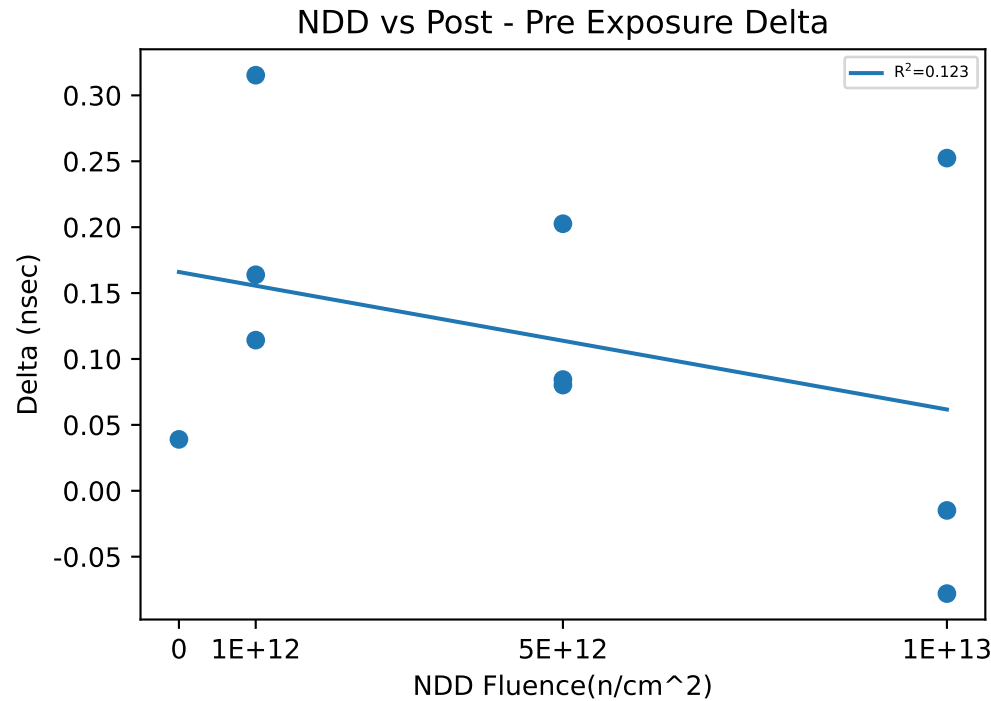
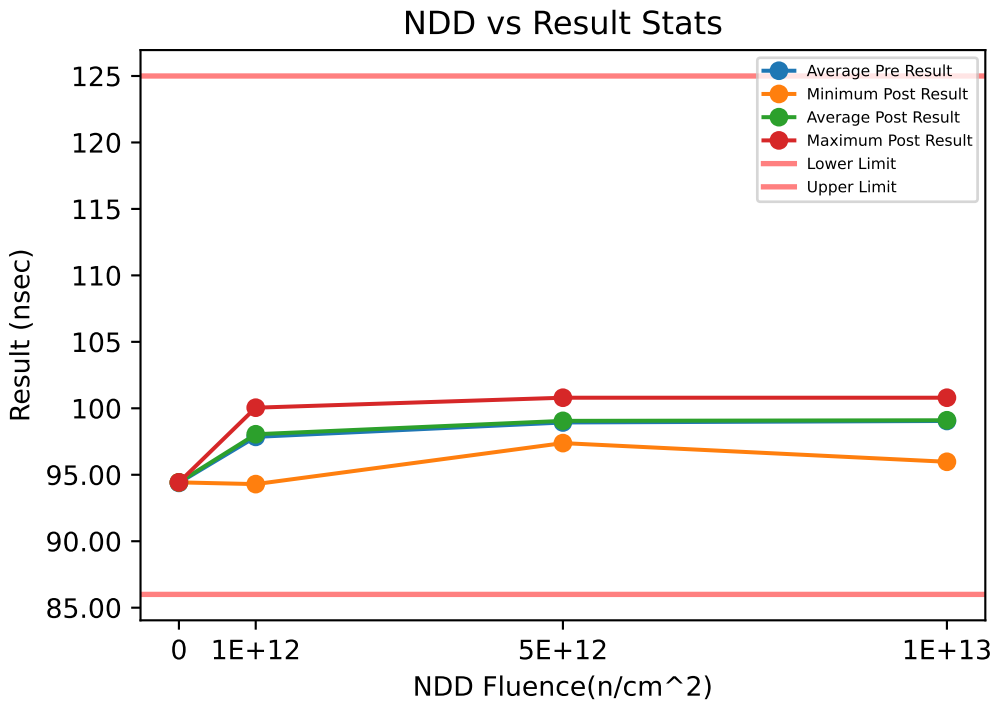
NDD vs Post - Pre Exposure Delta



Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	47.693	47.693	47.693		47.969	47.969	47.969		0.276	0.276	0.276	
1e+12	47.545	49.025	49.767	1.2818	47.818	49.274	50.01	1.2605	0.2262	0.24853	0.2732	0.023587
5e+12	48.723	49.397	50.029	0.65416	49.116	49.777	50.475	0.68051	0.3023	0.3802	0.4458	0.072536
1e+13	48.005	49.509	50.369	1.3073	48.365	49.726	50.67	1.2078	-0.0112	0.21637	0.3598	0.1993

Device Test: 96.28 T_RHL_MAX(DHL Dead Time Max 1MHz VIN_12V)



Test Results (Lower Limit = 86.0, Upper Limit = 125.0 (nsec))

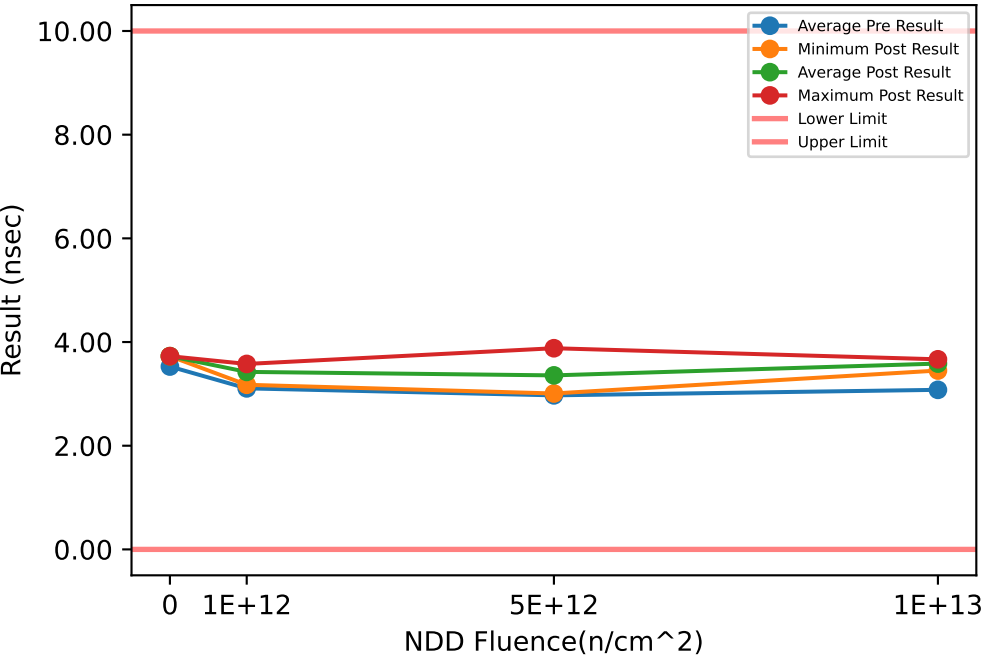
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	94.133	94.297	0.1639
551	1e+12	NDD	99.687	99.801	0.1143
552	1e+12	NDD	99.731	100.05	0.3153
553	5e+12	NDD	97.298	97.382	0.0844
554	5e+12	NDD	100.72	100.8	0.0802
555	5e+12	NDD	98.784	98.986	0.2026
556	1e+13	NDD	100.61	100.53	-0.078
557	1e+13	NDD	100.54	100.8	0.2524
558	1e+13	NDD	95.992	95.977	-0.0149
559	0	NDD, Ctrl	94.389	94.428	0.039

Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	94.389	94.389	94.389		94.428	94.428	94.428		0.039	0.039	0.039	
1e+12	94.133	97.85	99.731	3.2195	94.297	98.048	100.05	3.2511	0.1143	0.19783	0.3153	0.10471
5e+12	97.298	98.933	100.72	1.7138	97.382	99.055	100.8	1.7079	0.0802	0.1224	0.2026	0.069487
1e+13	95.992	99.047	100.61	2.6463	95.977	99.1	100.8	2.7084	-0.078	0.053167	0.2524	0.1754

Device Test: 96.29 T_RHL_MIN(DHL Dead Time Min 2MHz VIN_12V)

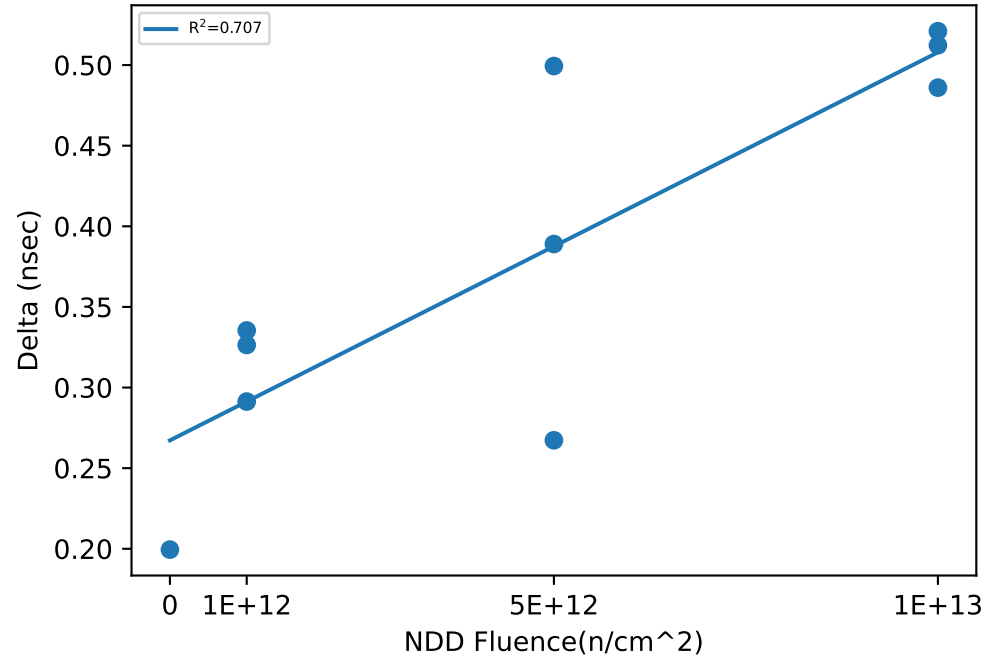
NDD vs Result Stats



Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	3.2278	3.5191	0.2913
551	1e+12	NDD	2.8492	3.1756	0.3264
552	1e+12	NDD	3.242	3.5774	0.3354
553	5e+12	NDD	3.3811	3.8805	0.4994
554	5e+12	NDD	2.7934	3.1824	0.389
555	5e+12	NDD	2.7403	3.0076	0.2673
556	1e+13	NDD	2.9642	3.4502	0.486
557	1e+13	NDD	3.1237	3.636	0.5123
558	1e+13	NDD	3.1459	3.6669	0.521
559	0	NDD, Ctrl	3.5275	3.727	0.1995

NDD vs Post - Pre Exposure Delta

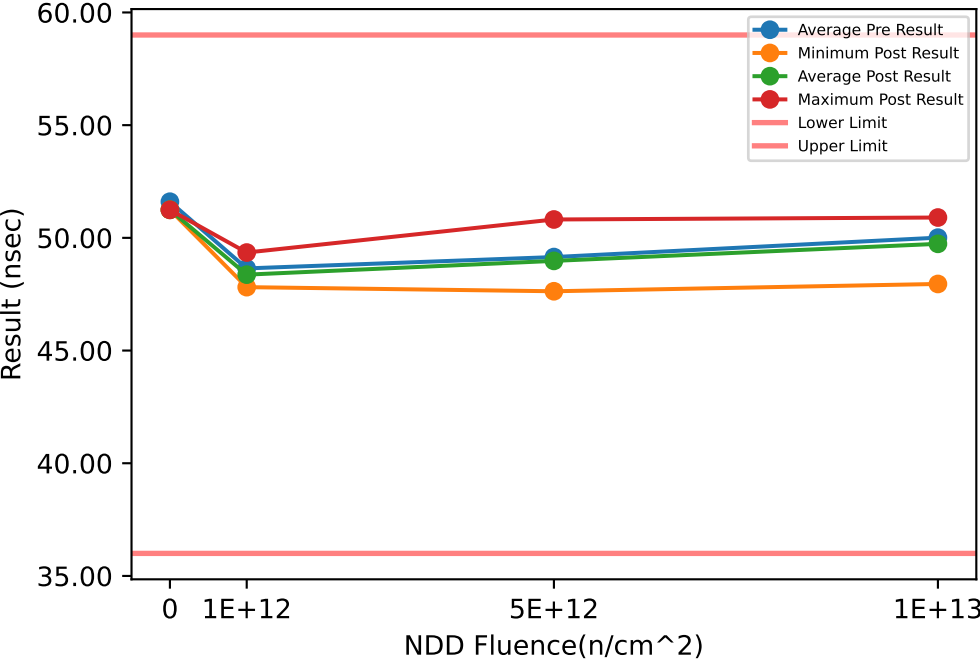


Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.5275	3.5275	3.5275		3.727	3.727	3.727		0.1995	0.1995	0.1995	
1e+12	2.8492	3.1063	3.242	0.2228	3.1756	3.424	3.5774	0.21712	0.2913	0.3177	0.3354	0.023302
5e+12	2.7403	2.9716	3.3811	0.35563	3.0076	3.3568	3.8805	0.46185	0.2673	0.38523	0.4994	0.1161
1e+13	2.9642	3.0779	3.1459	0.099119	3.4502	3.5844	3.6669	0.11721	0.486	0.50643	0.521	0.018223

Device Test: 96.3 T_RLH_LARGE(DLH Dead Time Large 500kHz VIN_12V)

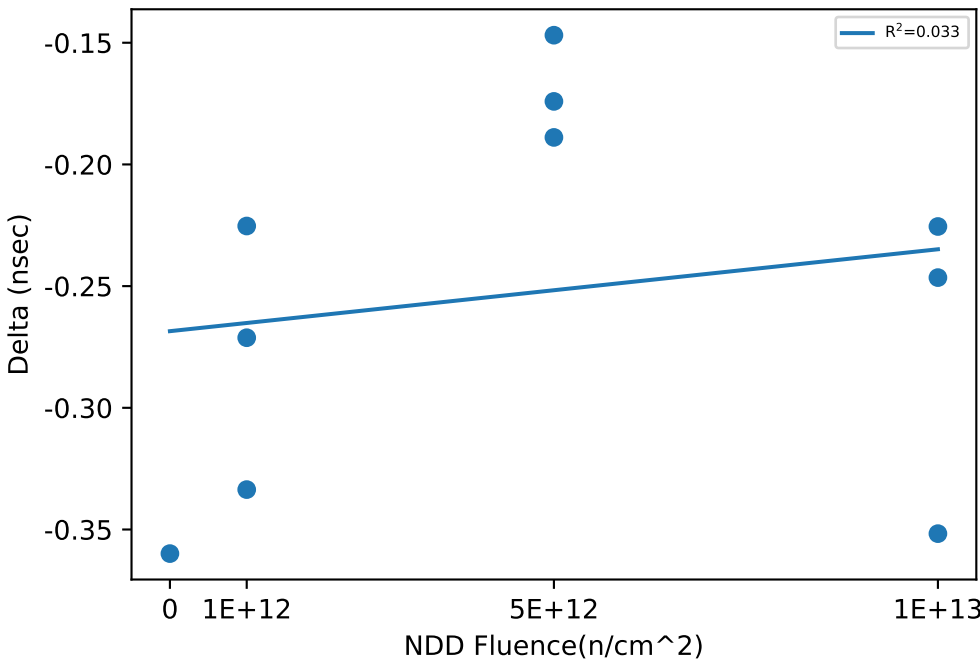
NDD vs Result Stats



Test Results (Lower Limit = 36.0, Upper Limit = 59.0 (nsec))

Serial #	Fluence(n/cm ²)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	48.167	47.942	-0.2253
551	1e+12	NDD	48.084	47.813	-0.2712
552	1e+12	NDD	49.682	49.348	-0.3336
553	5e+12	NDD	48.663	48.489	-0.1741
554	5e+12	NDD	47.819	47.63	-0.1889
555	5e+12	NDD	50.962	50.815	-0.1469
556	1e+13	NDD	48.306	47.954	-0.3517
557	1e+13	NDD	51.127	50.902	-0.2255
558	1e+13	NDD	50.593	50.347	-0.2465
559	0	NDD, Ctrl	51.603	51.243	-0.3599

NDD vs Post - Pre Exposure Delta

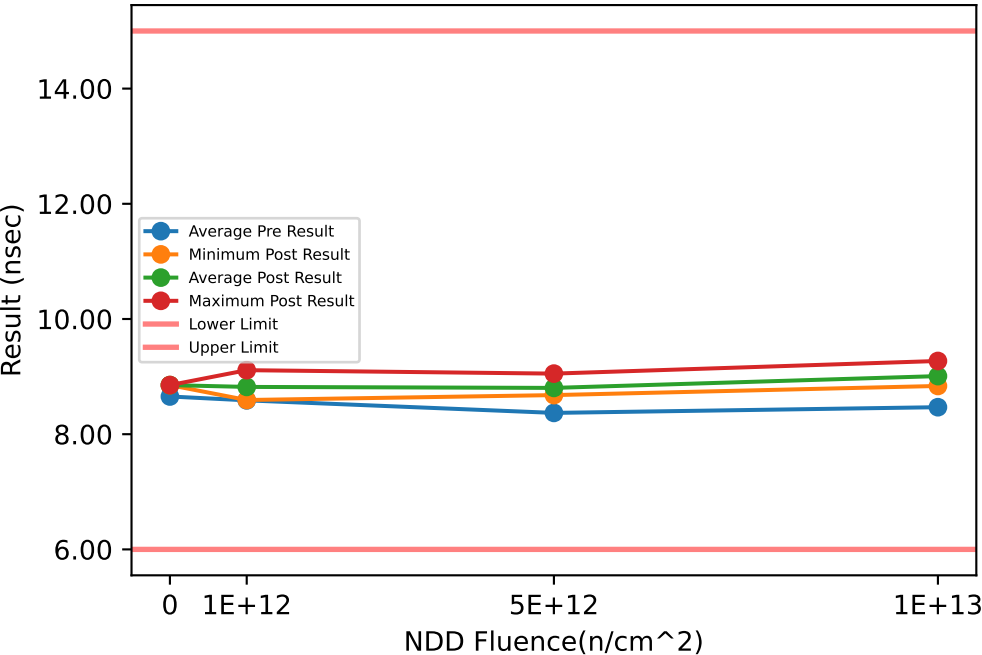


Test Statistics (nsec)

Fluence(n/cm ²)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	51.603	51.603	51.603		51.243	51.243	51.243		-0.3599	-0.3599	-0.3599	
1e+12	48.084	48.644	49.682	0.89949	47.813	48.368	49.348	0.8517	-0.3336	-0.2767	-0.2253	0.054359
5e+12	47.819	49.148	50.962	1.6267	47.63	48.978	50.815	1.6479	-0.1889	-0.16997	-0.1469	0.021303
1e+13	48.306	50.009	51.127	1.4989	47.954	49.734	50.902	1.5665	-0.3517	-0.27457	-0.2255	0.06762

Device Test: 96.30 T_RHL_SMALL(DHL Dead Time Small 2MHz VIN_12V)

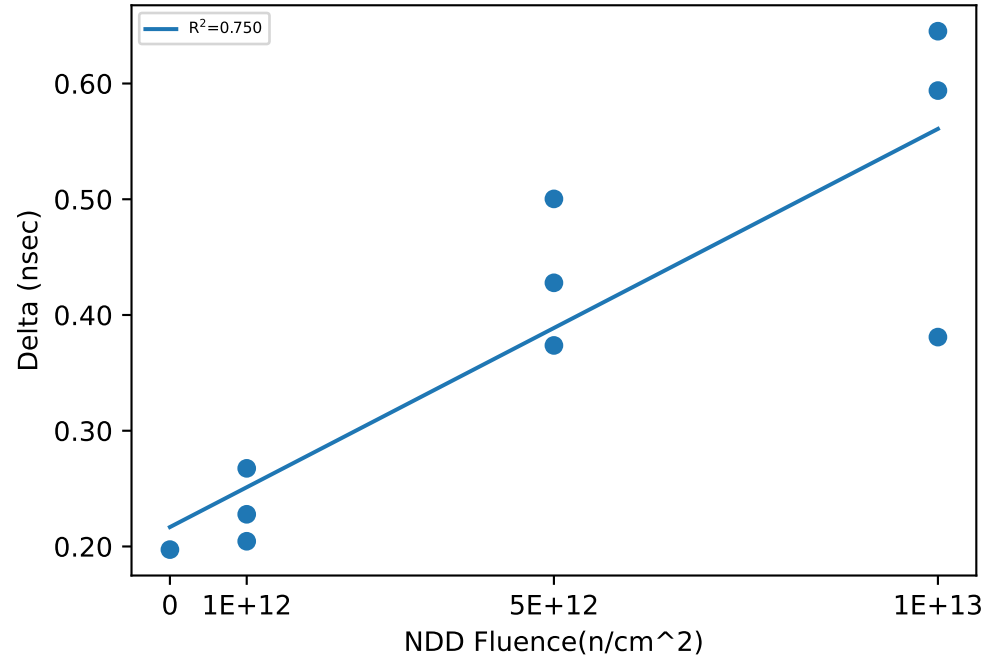
NDD vs Result Stats



Test Results (Lower Limit = 6.0, Upper Limit = 15.0 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	8.5535	8.758	0.2045
551	1e+12	NDD	8.3259	8.5934	0.2675
552	1e+12	NDD	8.8836	9.1114	0.2278
553	5e+12	NDD	8.6781	9.0518	0.3737
554	5e+12	NDD	8.2528	8.6806	0.4278
555	5e+12	NDD	8.1785	8.6788	0.5003
556	1e+13	NDD	8.4565	8.8374	0.3809
557	1e+13	NDD	8.6259	9.2711	0.6452
558	1e+13	NDD	8.3236	8.9175	0.5939
559	0	NDD, Ctrl	8.6547	8.852	0.1973

NDD vs Post - Pre Exposure Delta

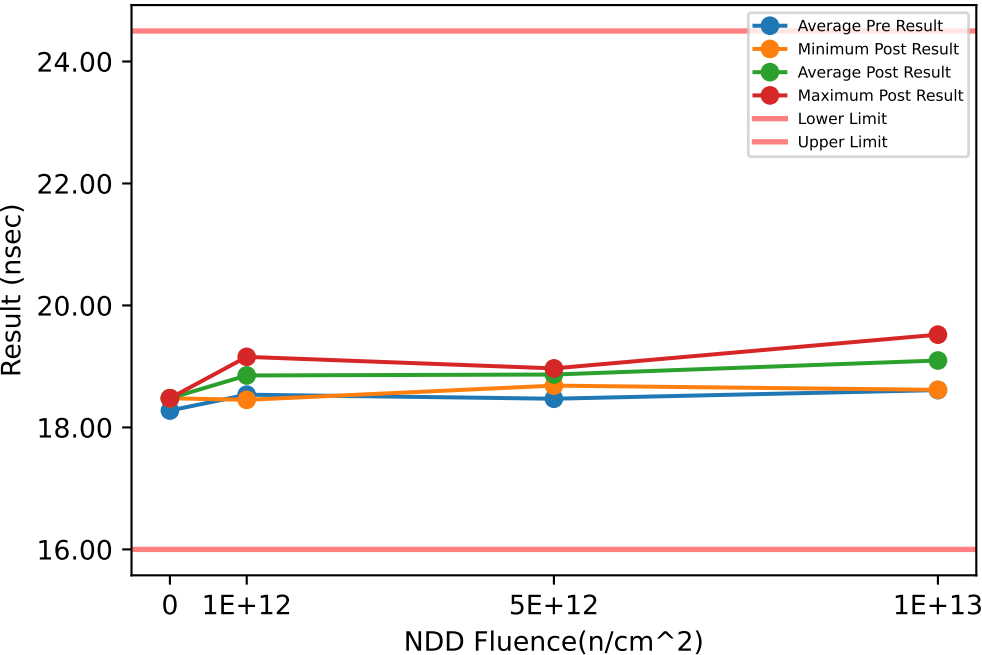


Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.6547	8.6547	8.6547		8.852	8.852	8.852		0.1973	0.1973	0.1973	
1e+12	8.3259	8.5877	8.8836	0.28042	8.5934	8.8209	9.1114	0.26467	0.2045	0.23327	0.2675	0.031854
5e+12	8.1785	8.3698	8.6781	0.26957	8.6788	8.8037	9.0518	0.21483	0.3737	0.43393	0.5003	0.063522
1e+13	8.3236	8.4687	8.6259	0.15152	8.8374	9.0087	9.2711	0.23078	0.3809	0.54	0.6452	0.14015

Device Test: 96.31 T_RHL_MID(DHL Dead Time Mid 2MHz VIN_12V)

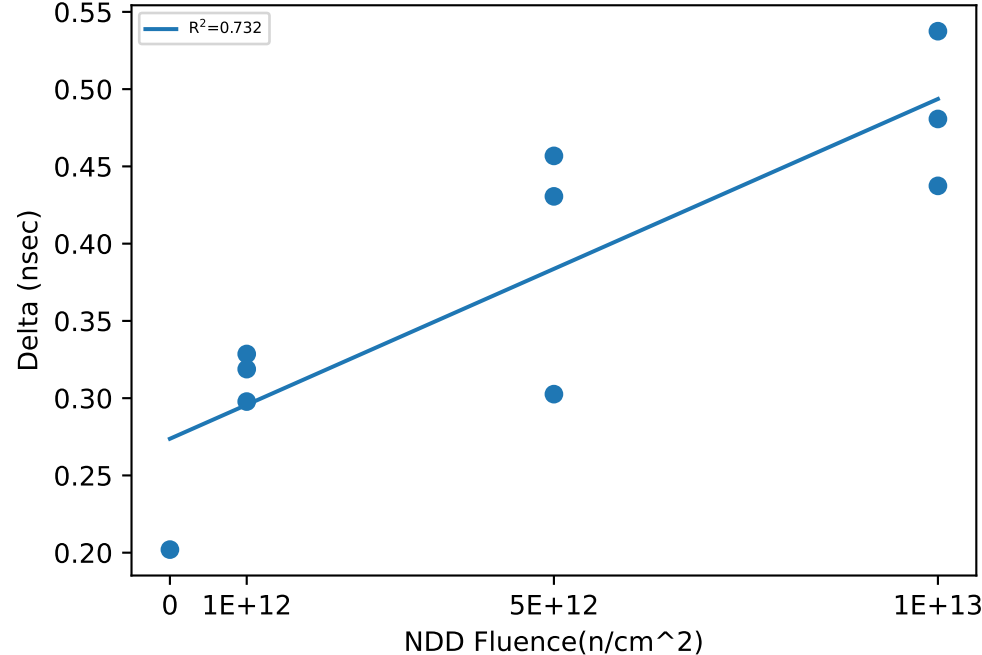
NDD vs Result Stats



Test Results (Lower Limit = 16.0, Upper Limit = 24.5 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	18.133	18.452	0.3188
551	1e+12	NDD	18.649	18.947	0.2978
552	1e+12	NDD	18.828	19.157	0.3286
553	5e+12	NDD	18.518	18.948	0.4306
554	5e+12	NDD	18.511	18.968	0.4568
555	5e+12	NDD	18.383	18.685	0.3026
556	1e+13	NDD	18.717	19.155	0.4374
557	1e+13	NDD	19.04	19.521	0.4807
558	1e+13	NDD	18.079	18.616	0.5375
559	0	NDD, Ctrl	18.276	18.479	0.202

NDD vs Post - Pre Exposure Delta

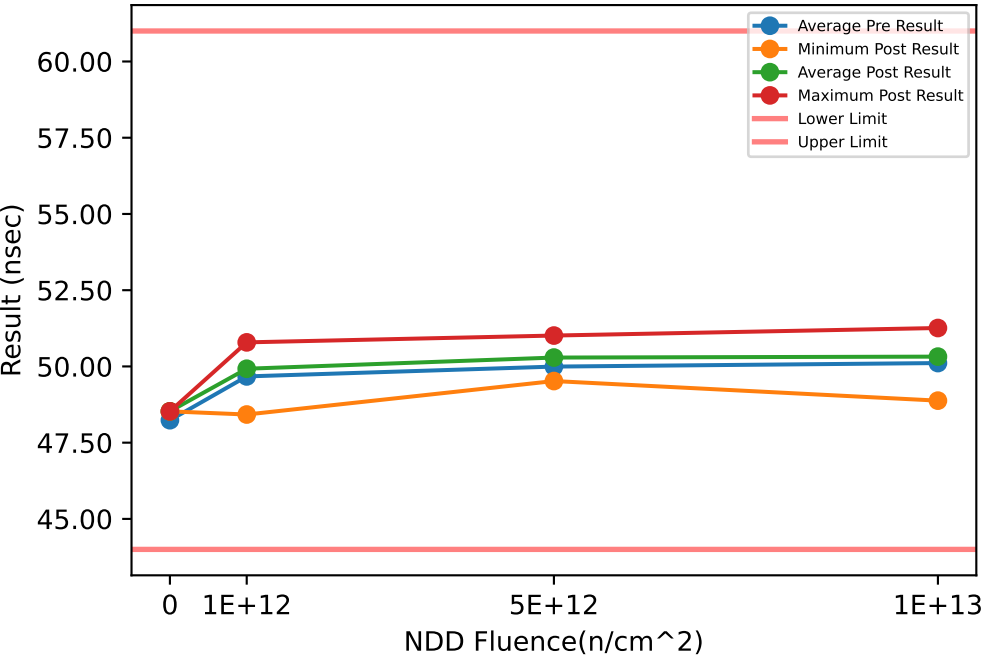


Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	18.276	18.276	18.276		18.479	18.479	18.479		0.202	0.202	0.202	
1e+12	18.133	18.537	18.828	0.36085	18.452	18.852	19.157	0.36189	0.2978	0.31507	0.3286	0.015736
5e+12	18.383	18.471	18.518	0.076051	18.685	18.867	18.968	0.15775	0.3026	0.39667	0.4568	0.082511
1e+13	18.079	18.612	19.04	0.48938	18.616	19.097	19.521	0.45514	0.4374	0.4852	0.5375	0.050201

Device Test: 96.32 T_RHL_LARGE(DHL Dead Time Large 2MHz VIN_12V)

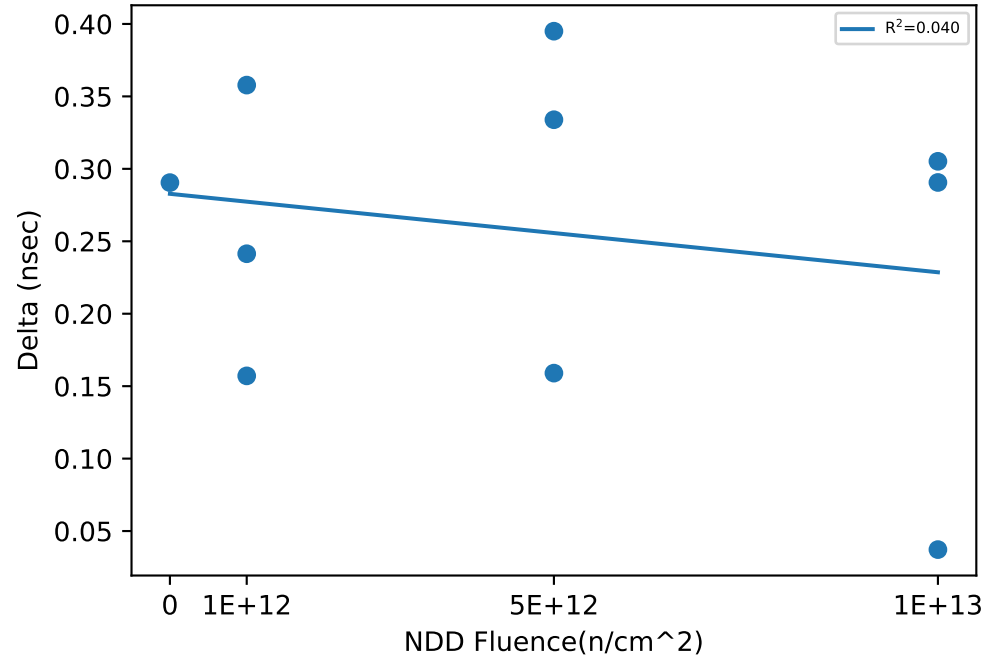
NDD vs Result Stats



Test Results (Lower Limit = 44.0, Upper Limit = 61.0 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	48.182	48.423	0.2414
551	1e+12	NDD	50.404	50.561	0.1571
552	1e+12	NDD	50.431	50.789	0.3578
553	5e+12	NDD	49.362	49.521	0.159
554	5e+12	NDD	50.618	51.013	0.395
555	5e+12	NDD	50.006	50.34	0.3339
556	1e+13	NDD	50.789	50.827	0.0372
557	1e+13	NDD	50.969	51.26	0.2906
558	1e+13	NDD	48.573	48.878	0.3052
559	0	NDD, Ctrl	48.236	48.527	0.2905

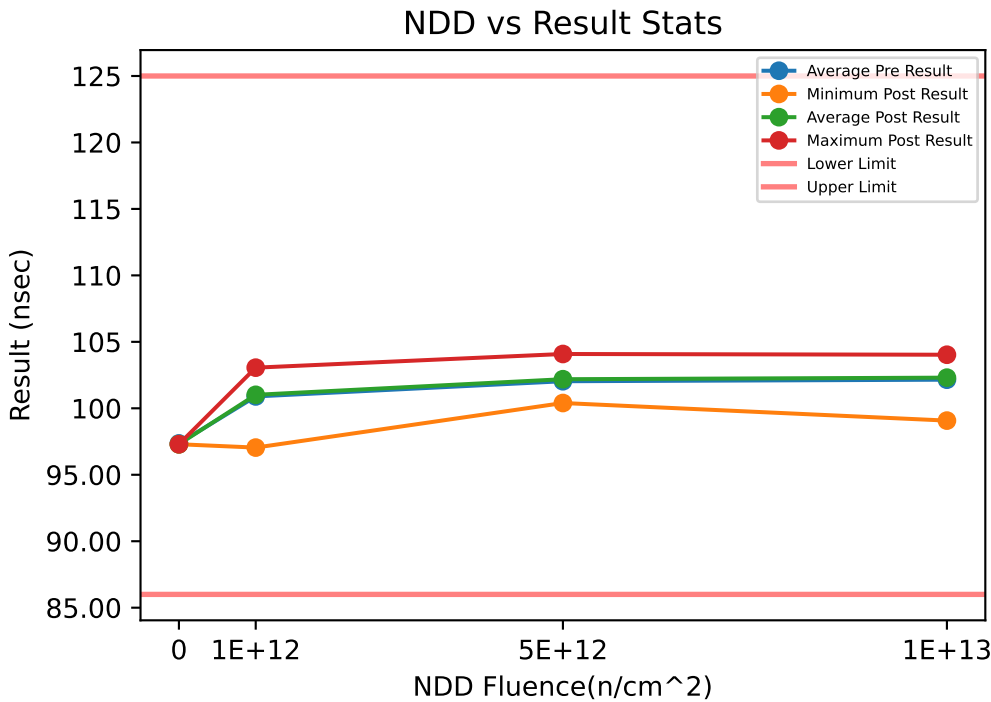
NDD vs Post - Pre Exposure Delta



Test Statistics (nsec)

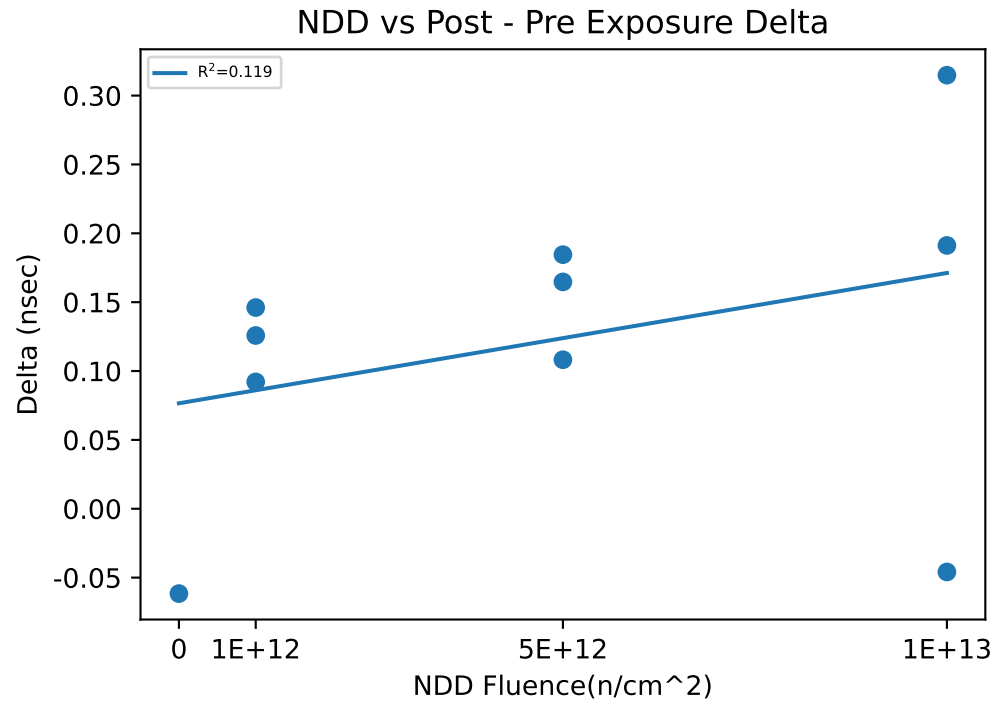
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	48.236	48.236	48.236		48.527	48.527	48.527		0.2905	0.2905	0.2905	
1e+12	48.182	49.673	50.431	1.291	48.423	49.925	50.789	1.3052	0.1571	0.2521	0.3578	0.10078
5e+12	49.362	49.995	50.618	0.62802	49.521	50.291	51.013	0.74713	0.159	0.29597	0.395	0.12249
1e+13	48.573	50.111	50.969	1.3347	48.878	50.322	51.26	1.2687	0.0372	0.211	0.3052	0.15069

Device Test: 96.33 T_RHL_MAX(DHL Dead Time Max 2MHz VIN_12V)



Test Results (Lower Limit = 86.0,
Upper Limit = 125.0 (nsec))

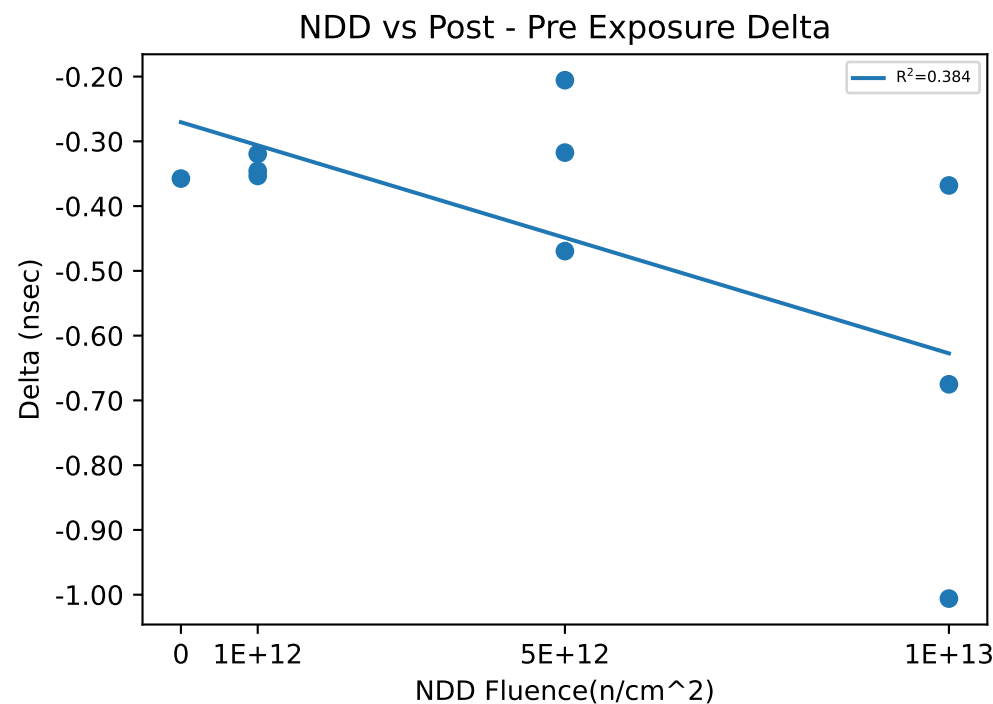
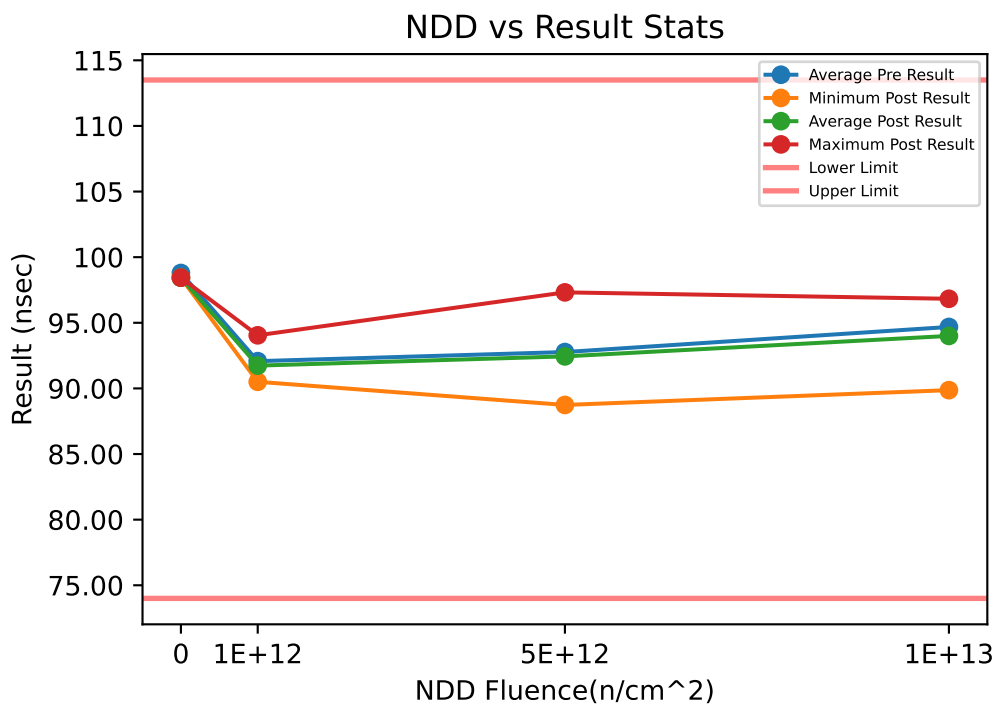
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	96.953	97.045	0.0921
551	1e+12	NDD	102.79	102.94	0.1461
552	1e+12	NDD	102.93	103.06	0.1258
553	5e+12	NDD	100.23	100.4	0.1647
554	5e+12	NDD	103.98	104.09	0.1082
555	5e+12	NDD	101.9	102.08	0.1845
556	1e+13	NDD	103.86	103.81	-0.0459
557	1e+13	NDD	103.72	104.03	0.3148
558	1e+13	NDD	98.884	99.075	0.1912
559	0	NDD, Ctrl	97.359	97.297	-0.0616



Test Statistics (nsec)

Fluence(n/cm ²)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	97.359	97.359	97.359		97.297	97.297	97.297		-0.0616	-0.0616	-0.0616	
1e+12	96.953	100.89	102.93	3.4131	97.045	101.01	103.06	3.4383	0.0921	0.12133	0.1461	0.027276
5e+12	100.23	102.04	103.98	1.8762	100.4	102.19	104.09	1.8464	0.1082	0.15247	0.1845	0.039594
1e+13	98.884	102.15	103.86	2.8318	99.075	102.31	104.03	2.8003	-0.0459	0.15337	0.3148	0.1833

Device Test: 96.4 T_RLH_MAX(DLH Dead Time Max 500kHz VIN_12V)



Test Results (Lower Limit = 74.0, Upper Limit = 113.5 (nsec))

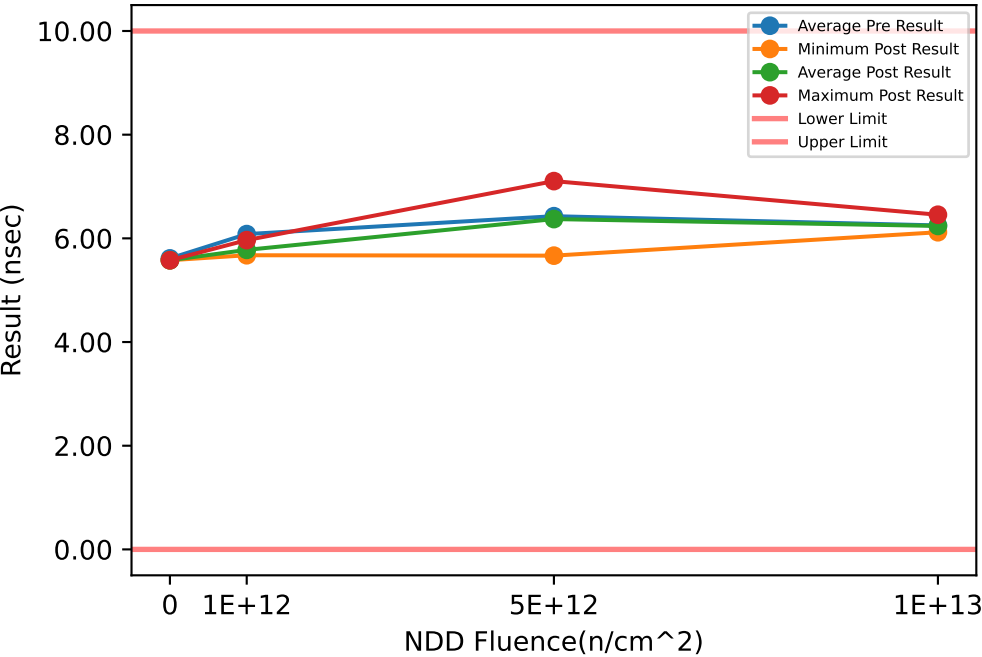
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	91.013	90.66	-0.3534
551	1e+12	NDD	90.85	90.504	-0.3456
552	1e+12	NDD	94.366	94.047	-0.3194
553	5e+12	NDD	91.468	91.262	-0.2056
554	5e+12	NDD	89.209	88.739	-0.4695
555	5e+12	NDD	97.635	97.318	-0.3174
556	1e+13	NDD	90.236	89.868	-0.3681
557	1e+13	NDD	97.504	96.829	-0.6751
558	1e+13	NDD	96.306	95.3	-1.006
559	0	NDD, Ctrl	98.795	98.437	-0.3575

Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	98.795	98.795	98.795		98.437	98.437	98.437		-0.3575	-0.3575	-0.3575	
1e+12	90.85	92.076	94.366	1.9845	90.504	91.737	94.047	2.0017	-0.3534	-0.33947	-0.3194	0.01781
5e+12	89.209	92.771	97.635	4.3617	88.739	92.44	97.318	4.4089	-0.4695	-0.33083	-0.2056	0.13246
1e+13	90.236	94.682	97.504	3.897	89.868	93.999	96.829	3.6586	-1.006	-0.68307	-0.3681	0.31902

Device Test: 96.5 T_RLH_MIN(DLH Dead Time Min 1MHz VIN_12V)

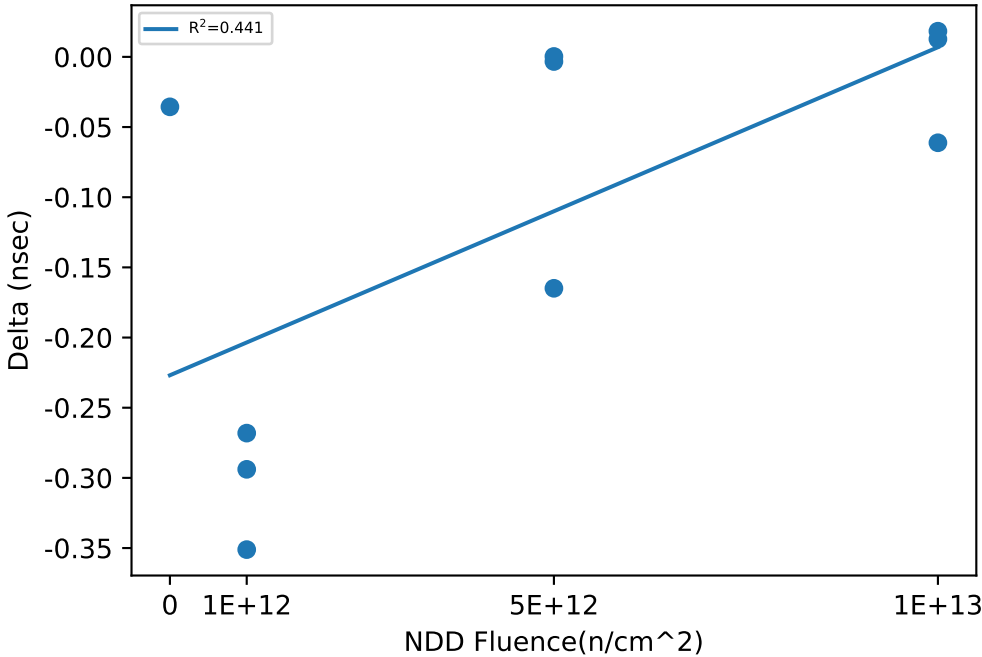
NDD vs Result Stats



Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	6.3171	5.966	-0.3511
551	1e+12	NDD	5.9681	5.6742	-0.2939
552	1e+12	NDD	5.9614	5.6933	-0.2681
553	5e+12	NDD	6.3442	6.3445	0.0003
554	5e+12	NDD	7.2692	7.1043	-0.1649
555	5e+12	NDD	5.6699	5.6666	-0.0033
556	1e+13	NDD	6.4428	6.4555	0.0127
557	1e+13	NDD	6.0996	6.1179	0.0183
558	1e+13	NDD	6.2059	6.1447	-0.0612
559	0	NDD, Ctrl	5.6135	5.5779	-0.0356

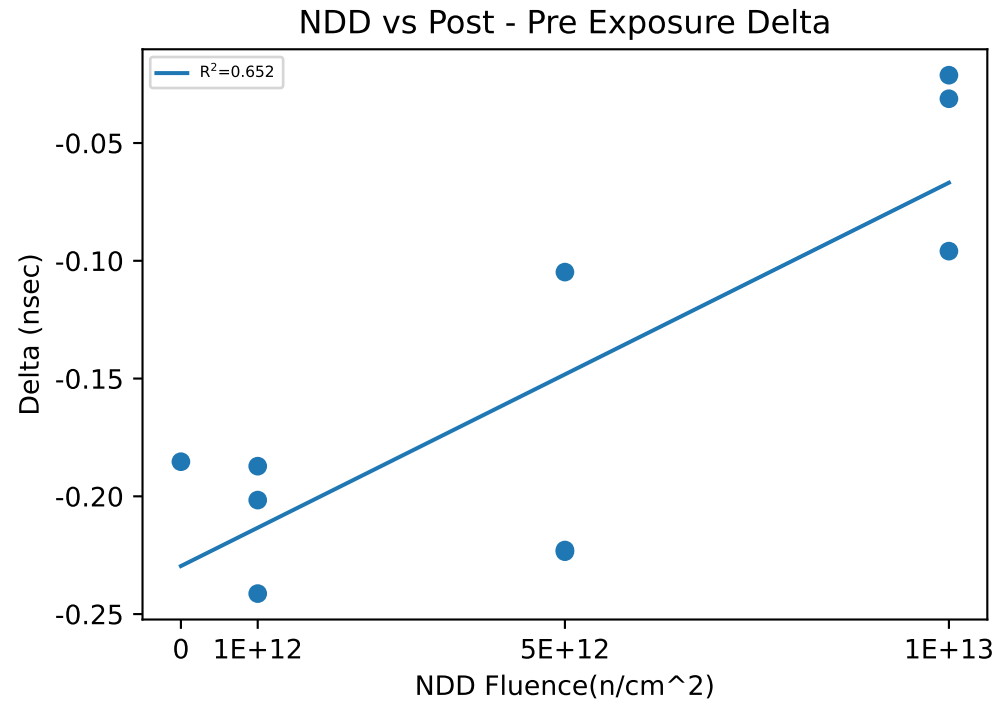
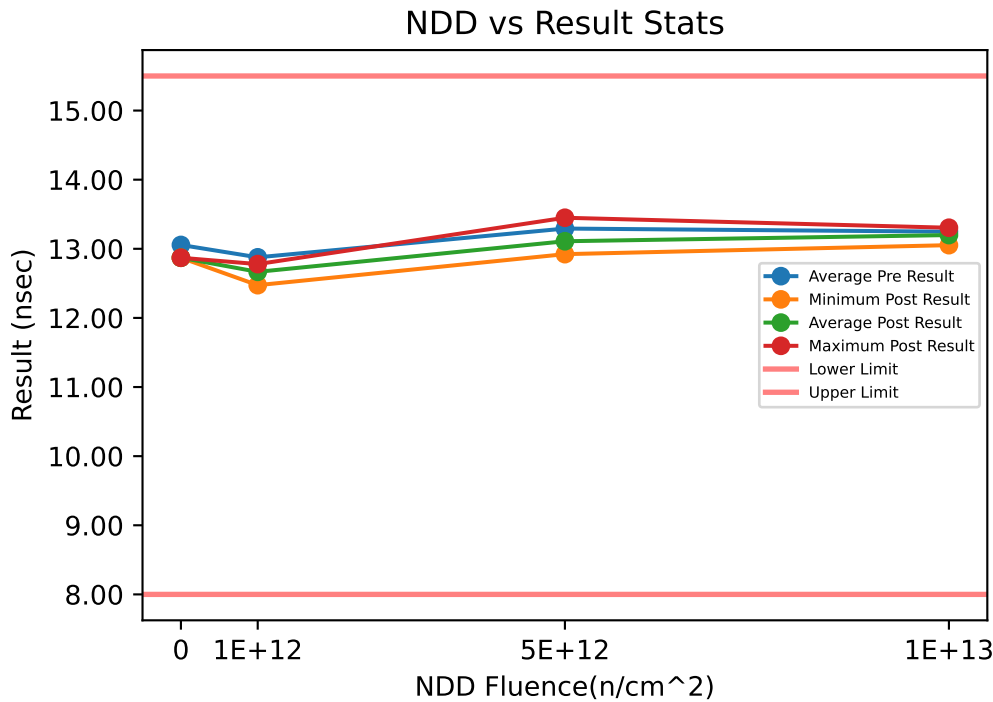
NDD vs Post - Pre Exposure Delta



Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.6135	5.6135	5.6135		5.5779	5.5779	5.5779		-0.0356	-0.0356	-0.0356	
1e+12	5.9614	6.0822	6.3171	0.20346	5.6742	5.7778	5.966	0.16324	-0.3511	-0.30437	-0.2681	0.042478
5e+12	5.6699	6.4278	7.2692	0.80292	5.6666	6.3718	7.1043	0.71924	-0.1649	-0.055967	0.0003	0.094356
1e+13	6.0996	6.2494	6.4428	0.17569	6.1179	6.2394	6.4555	0.18766	-0.0612	-0.010067	0.0183	0.044371

Device Test: 96.6 T_RLH_SMALL(DLH Dead Time Small 1MHz VIN_12V)



Test Results (Lower Limit = 8.0,
Upper Limit = 15.5 (nsec))

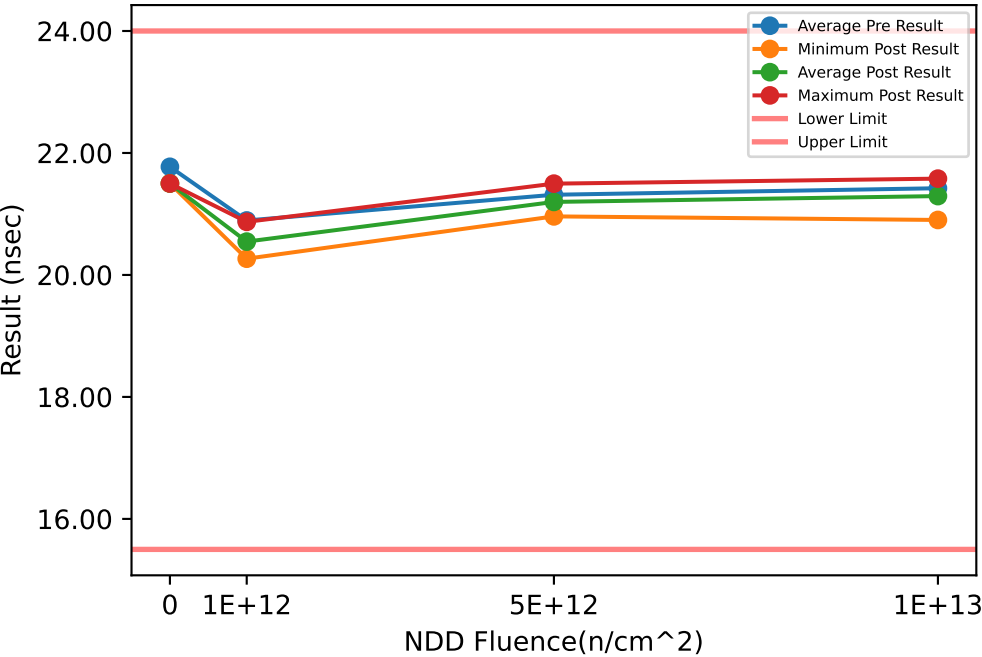
Serial #	Fluence(n/cm ²)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	12.935	12.748	-0.1872
551	1e+12	NDD	12.715	12.474	-0.2413
552	1e+12	NDD	12.98	12.779	-0.2016
553	5e+12	NDD	13.179	12.956	-0.2228
554	5e+12	NDD	13.673	13.449	-0.2235
555	5e+12	NDD	13.027	12.922	-0.1048
556	1e+13	NDD	13.149	13.053	-0.0959
557	1e+13	NDD	13.336	13.305	-0.0312
558	1e+13	NDD	13.259	13.238	-0.0212
559	0	NDD, Ctrl	13.056	12.87	-0.1853

Test Statistics (nsec)

Fluence(n/cm ²)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	13.056	13.056	13.056		12.87	12.87	12.87		-0.1853	-0.1853	-0.1853	
1e+12	12.715	12.877	12.98	0.14188	12.474	12.667	12.779	0.16785	-0.2413	-0.21003	-0.1872	0.028019
5e+12	13.027	13.293	13.673	0.33752	12.922	13.109	13.449	0.29492	-0.2235	-0.1837	-0.1048	0.06833
1e+13	13.149	13.248	13.336	0.094172	13.053	13.199	13.305	0.1306	-0.0959	-0.049433	-0.0212	0.040551

Device Test: 96.7 T_RLH_MID(DLH Dead Time Mid 1MHz VIN_12V)

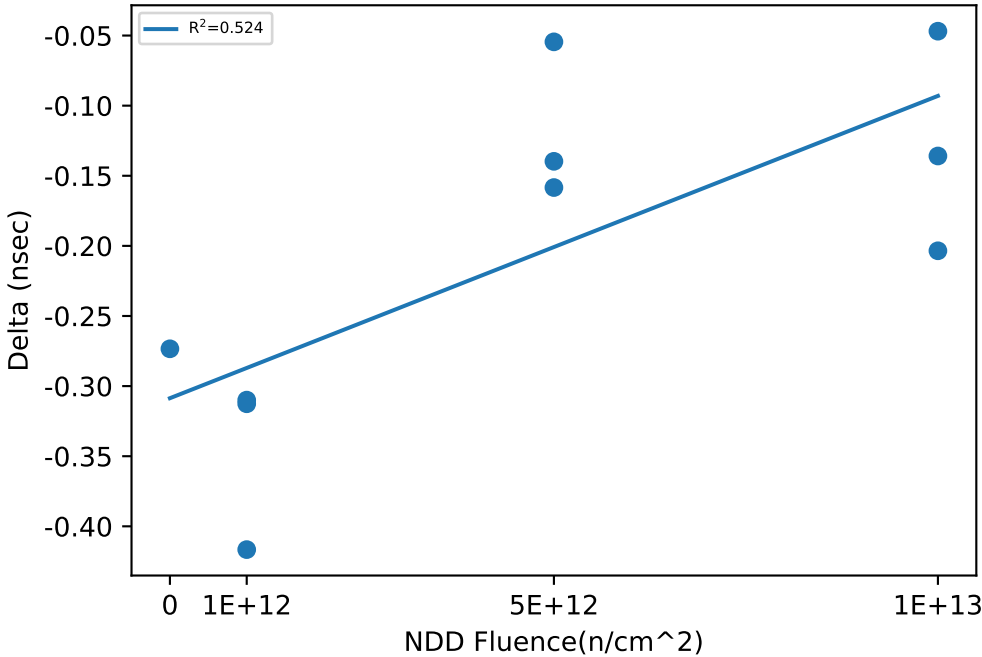
NDD vs Result Stats



Test Results (Lower Limit = 15.5, Upper Limit = 24.0 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	20.814	20.504	-0.31
551	1e+12	NDD	20.683	20.266	-0.4166
552	1e+12	NDD	21.183	20.87	-0.3126
553	5e+12	NDD	21.119	20.96	-0.1584
554	5e+12	NDD	21.275	21.135	-0.1397
555	5e+12	NDD	21.552	21.497	-0.0545
556	1e+13	NDD	20.949	20.902	-0.0469
557	1e+13	NDD	21.715	21.579	-0.1359
558	1e+13	NDD	21.602	21.398	-0.2035
559	0	NDD, Ctrl	21.773	21.5	-0.2734

NDD vs Post - Pre Exposure Delta

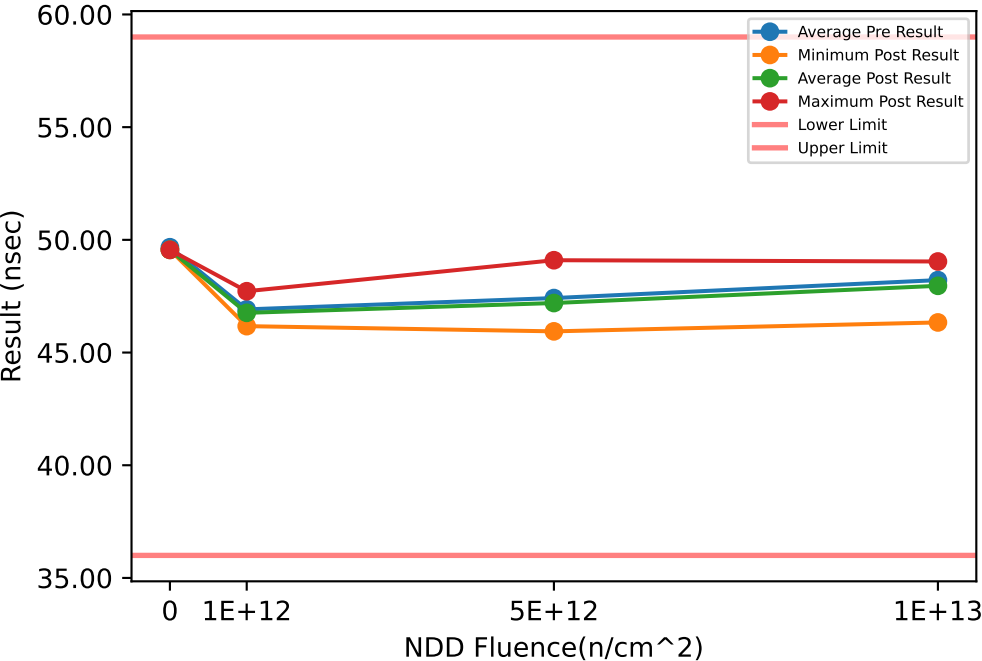


Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	21.773	21.773	21.773		21.5	21.5	21.5		-0.2734	-0.2734	-0.2734	
1e+12	20.683	20.893	21.183	0.25931	20.266	20.547	20.87	0.3043	-0.4166	-0.3464	-0.31	0.060809
5e+12	21.119	21.315	21.552	0.21925	20.96	21.197	21.497	0.2738	-0.1584	-0.11753	-0.0545	0.055383
1e+13	20.949	21.422	21.715	0.41374	20.902	21.293	21.579	0.35078	-0.2035	-0.12877	-0.0469	0.078543

Device Test: 96.8 T_RLH_LARGE(DLH Dead Time Large 1MHz VIN_12V)

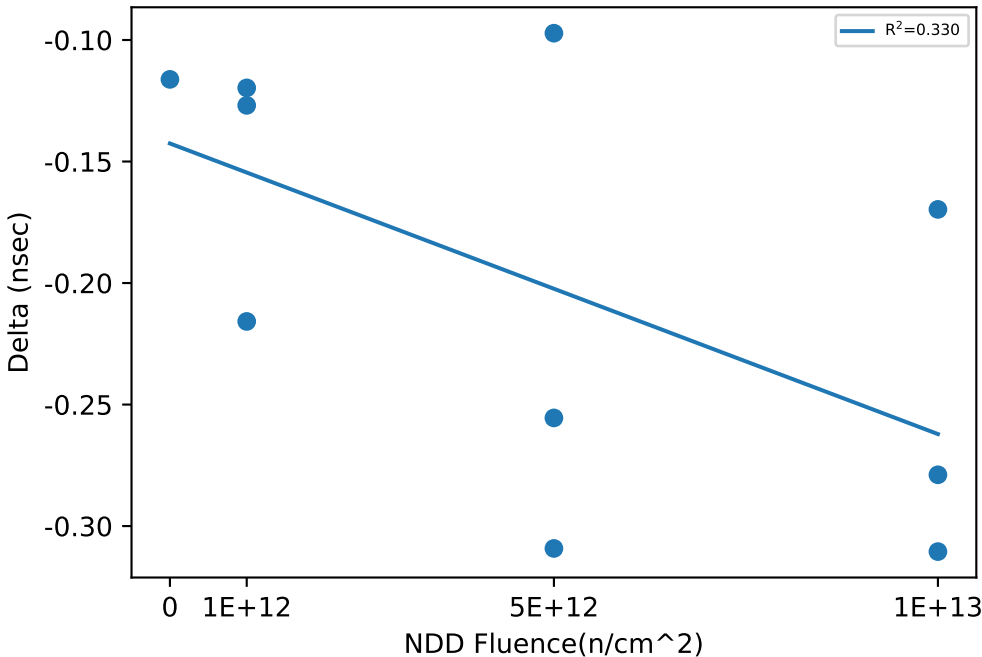
NDD vs Result Stats



Test Results (Lower Limit = 36.0, Upper Limit = 59.0 (nsec))

Serial #	Fluence(n/cm ²)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	46.512	46.392	-0.1197
551	1e+12	NDD	46.298	46.172	-0.1269
552	1e+12	NDD	47.937	47.721	-0.2158
553	5e+12	NDD	46.809	46.553	-0.2555
554	5e+12	NDD	46.249	45.94	-0.3092
555	5e+12	NDD	49.193	49.096	-0.0972
556	1e+13	NDD	46.505	46.336	-0.1697
557	1e+13	NDD	49.319	49.04	-0.2789
558	1e+13	NDD	48.816	48.506	-0.3105
559	0	NDD, Ctrl	49.672	49.556	-0.1162

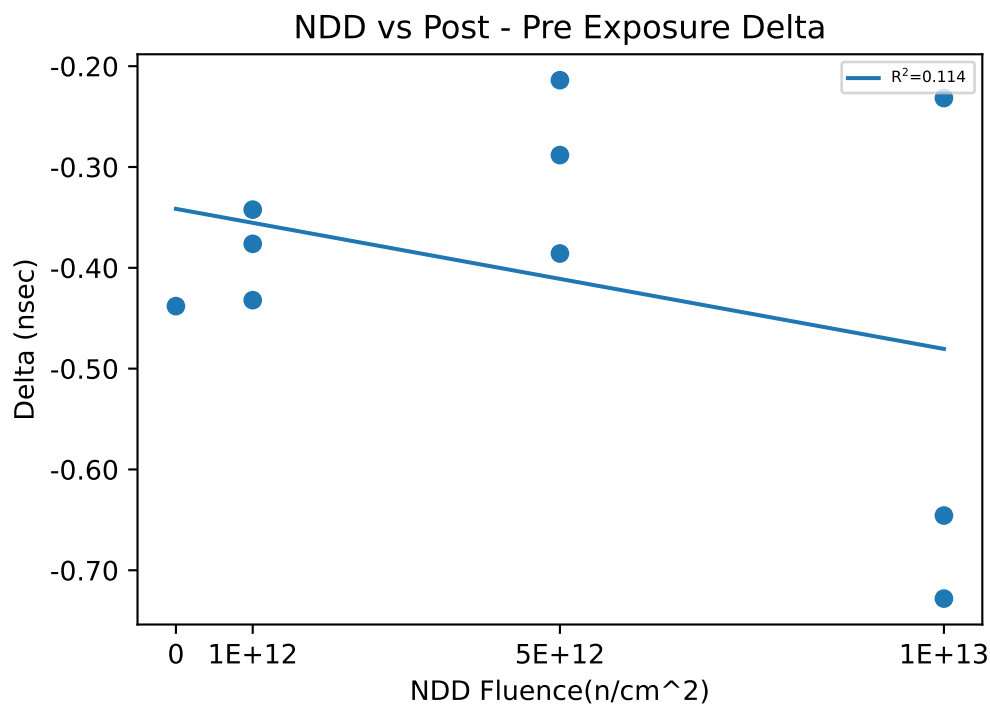
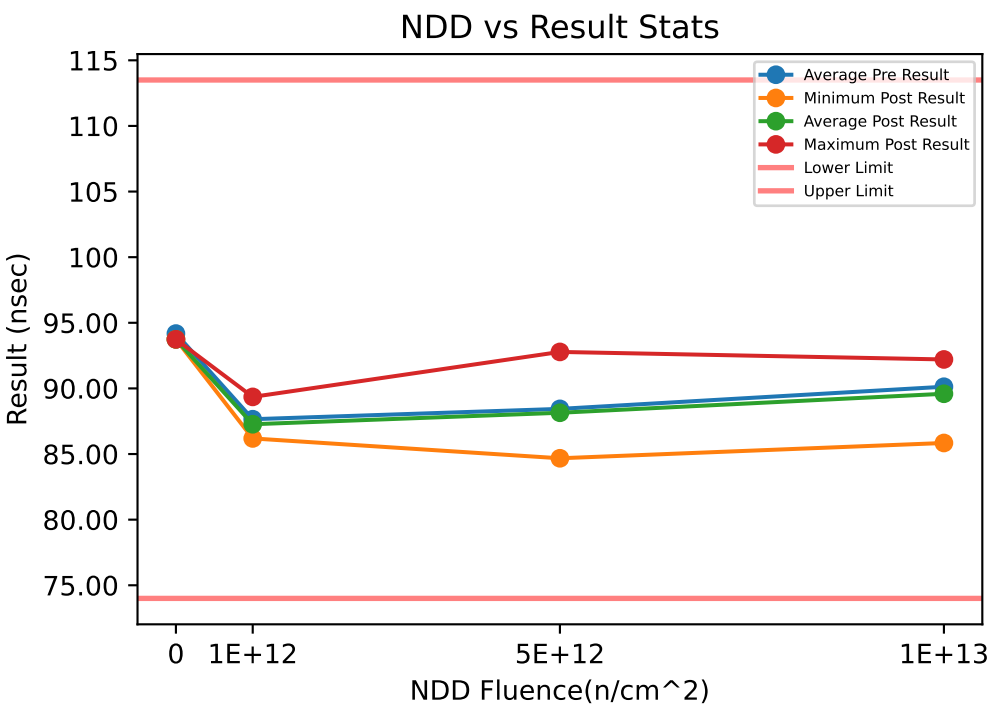
NDD vs Post - Pre Exposure Delta



Test Statistics (nsec)

Fluence(n/cm ²)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	49.672	49.672	49.672		49.556	49.556	49.556		-0.1162	-0.1162	-0.1162	
1e+12	46.298	46.916	47.937	0.89048	46.172	46.762	47.721	0.83795	-0.2158	-0.15413	-0.1197	0.053526
5e+12	46.249	47.417	49.193	1.5634	45.94	47.197	49.096	1.6734	-0.3092	-0.22063	-0.0972	0.11022
1e+13	46.505	48.214	49.319	1.5005	46.336	47.961	49.04	1.4323	-0.3105	-0.25303	-0.1697	0.073878

Device Test: 96.9 T_RLH_MAX(DLH Dead Time Max 1MHz VIN_12V)



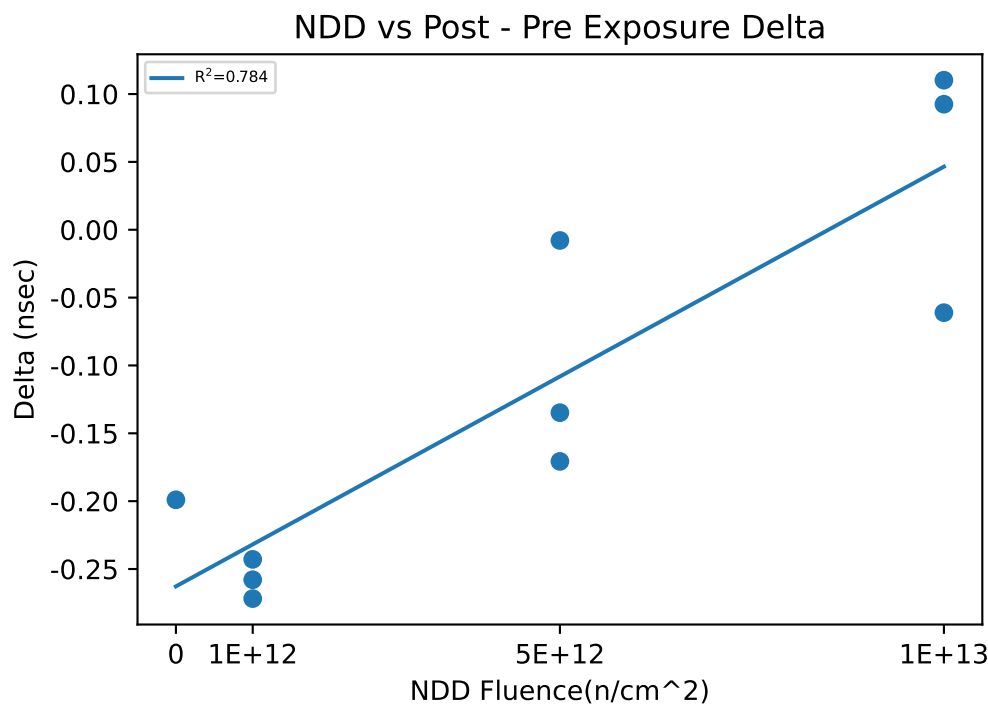
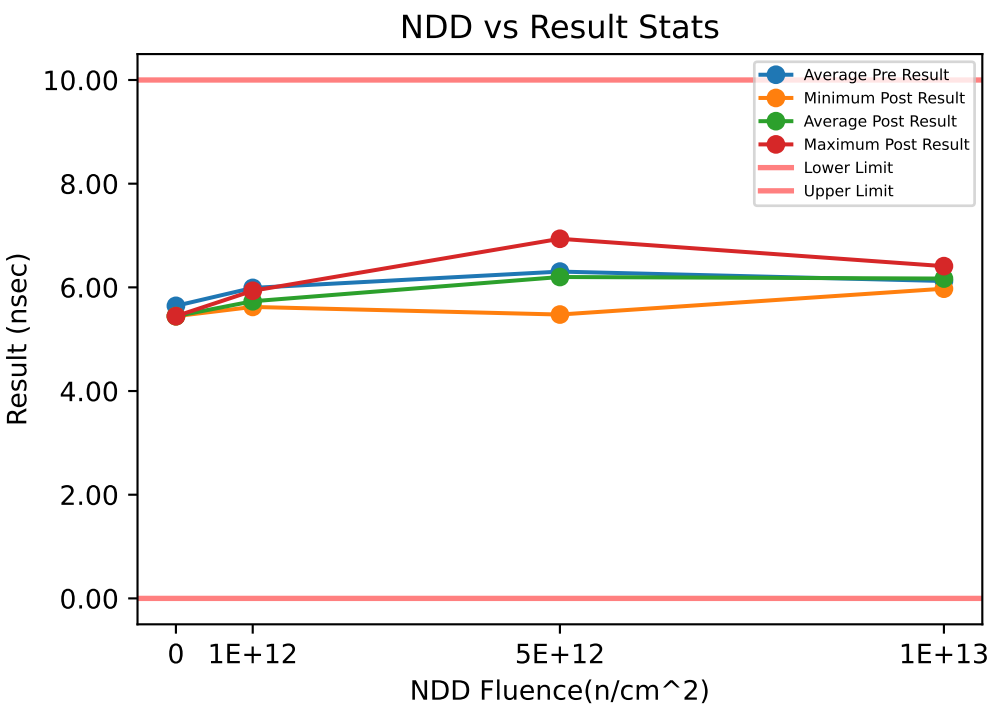
Test Results (Lower Limit = 74.0, Upper Limit = 113.5 (nsec))

Serial #	Fluence(n/cm ²)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	86.609	86.266	-0.3423
551	1e+12	NDD	86.565	86.189	-0.3762
552	1e+12	NDD	89.786	89.353	-0.4321
553	5e+12	NDD	87.19	86.976	-0.2139
554	5e+12	NDD	85.063	84.677	-0.3858
555	5e+12	NDD	93.068	92.78	-0.2882
556	1e+13	NDD	86.074	85.842	-0.2316
557	1e+13	NDD	92.853	92.207	-0.6457
558	1e+13	NDD	91.454	90.726	-0.7281
559	0	NDD, Ctrl	94.179	93.741	-0.438

Test Statistics (nsec)

Fluence(n/cm ²)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	94.179	94.179	94.179		93.741	93.741	93.741		-0.438	-0.438	-0.438	
1e+12	86.565	87.653	89.786	1.847	86.189	87.269	89.353	1.8052	-0.4321	-0.38353	-0.3423	0.045347
5e+12	85.063	88.44	93.068	4.1465	84.677	88.144	92.78	4.1758	-0.3858	-0.29597	-0.2139	0.086213
1e+13	86.074	90.127	92.853	3.5792	85.842	89.592	92.207	3.3307	-0.7281	-0.53513	-0.2316	0.26608

Device Test: 97.0 T_RLH_MIN(DLH Dead Time Min 500kHz VIN_14V)



Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (nsec))

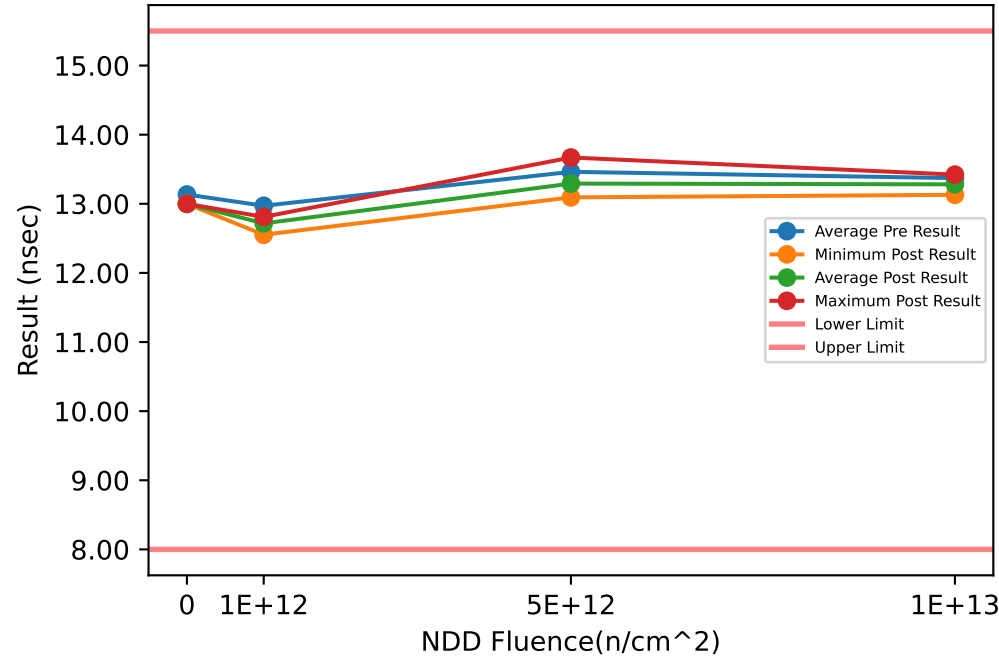
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	6.1918	5.9339	-0.2579
551	1e+12	NDD	5.911	5.6392	-0.2718
552	1e+12	NDD	5.8655	5.6226	-0.2429
553	5e+12	NDD	6.194	6.1861	-0.0079
554	5e+12	NDD	7.1078	6.9371	-0.1707
555	5e+12	NDD	5.6105	5.4757	-0.1348
556	1e+13	NDD	6.299	6.4092	0.1102
557	1e+13	NDD	6.0353	5.9742	-0.0611
558	1e+13	NDD	6.0332	6.1257	0.0925
559	0	NDD, Ctrl	5.6433	5.4443	-0.199

Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.6433	5.6433	5.6433		5.4443	5.4443	5.4443		-0.199	-0.199	-0.199	
1e+12	5.8655	5.9894	6.1918	0.17673	5.6226	5.7319	5.9339	0.17513	-0.2718	-0.25753	-0.2429	0.014453
5e+12	5.6105	6.3041	7.1078	0.7547	5.4757	6.1996	6.9371	0.73079	-0.1707	-0.10447	-0.0079	0.085534
1e+13	6.0332	6.1225	6.299	0.15286	5.9742	6.1697	6.4092	0.22081	-0.0611	0.0472	0.1102	0.094207

Device Test: 97.1 T_RLH_SMALL(DLH Dead Time Small 500kHz VIN_14V)

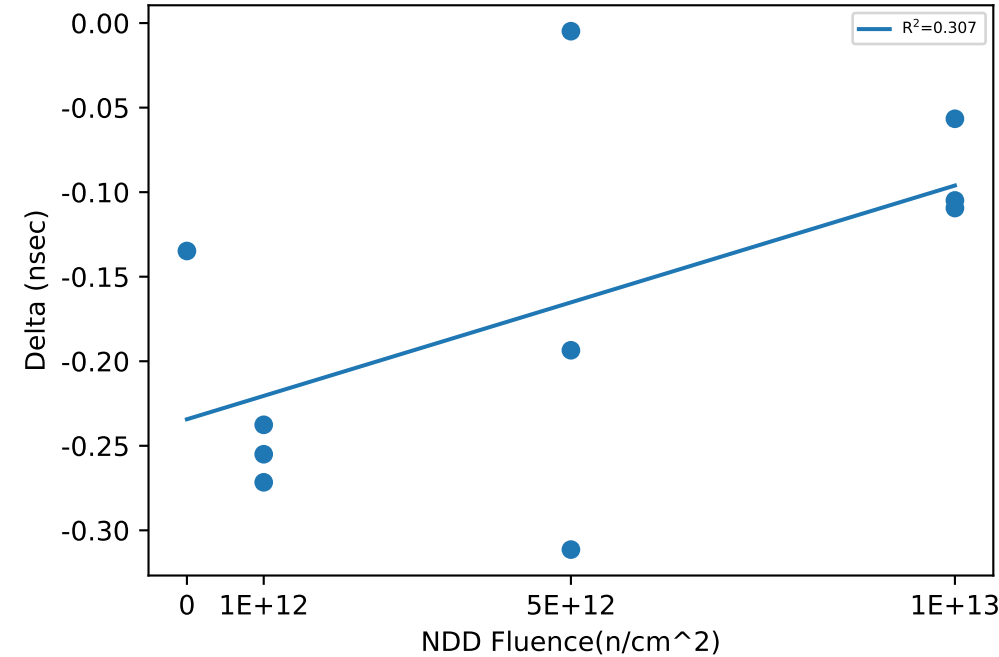
NDD vs Result Stats



Test Results (Lower Limit = 8.0, Upper Limit = 15.5 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	13.025	12.787	-0.2376
551	1e+12	NDD	12.824	12.552	-0.2716
552	1e+12	NDD	13.065	12.81	-0.255
553	5e+12	NDD	13.287	13.093	-0.1935
554	5e+12	NDD	13.981	13.67	-0.3114
555	5e+12	NDD	13.119	13.114	-0.0048
556	1e+13	NDD	13.235	13.13	-0.1049
557	1e+13	NDD	13.479	13.422	-0.0566
558	1e+13	NDD	13.402	13.292	-0.1094
559	0	NDD, Ctrl	13.134	12.999	-0.1348

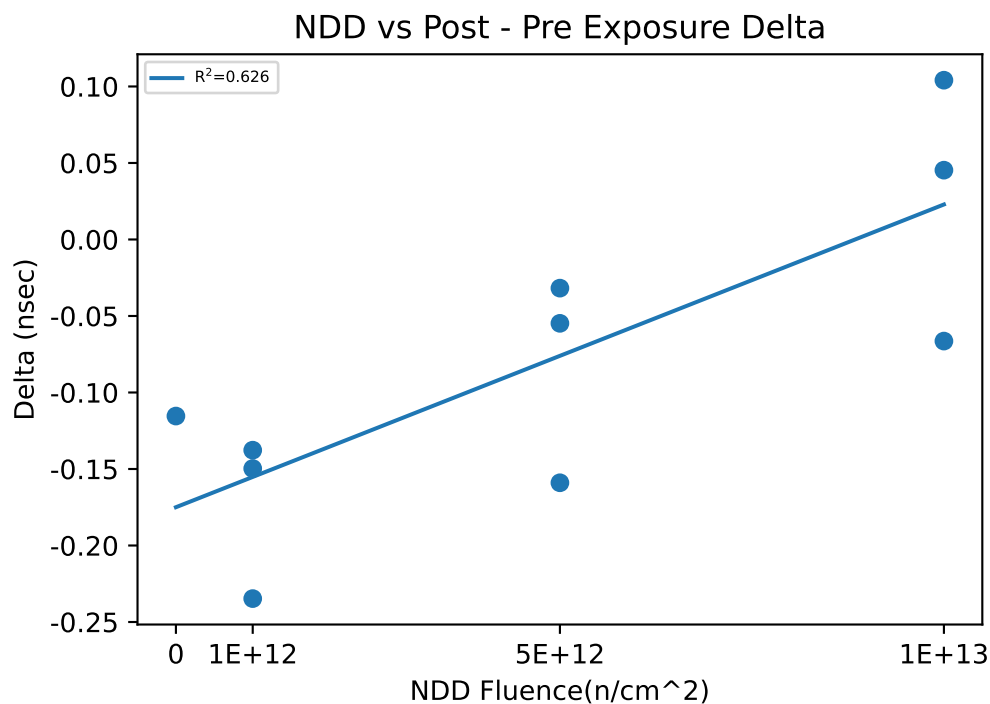
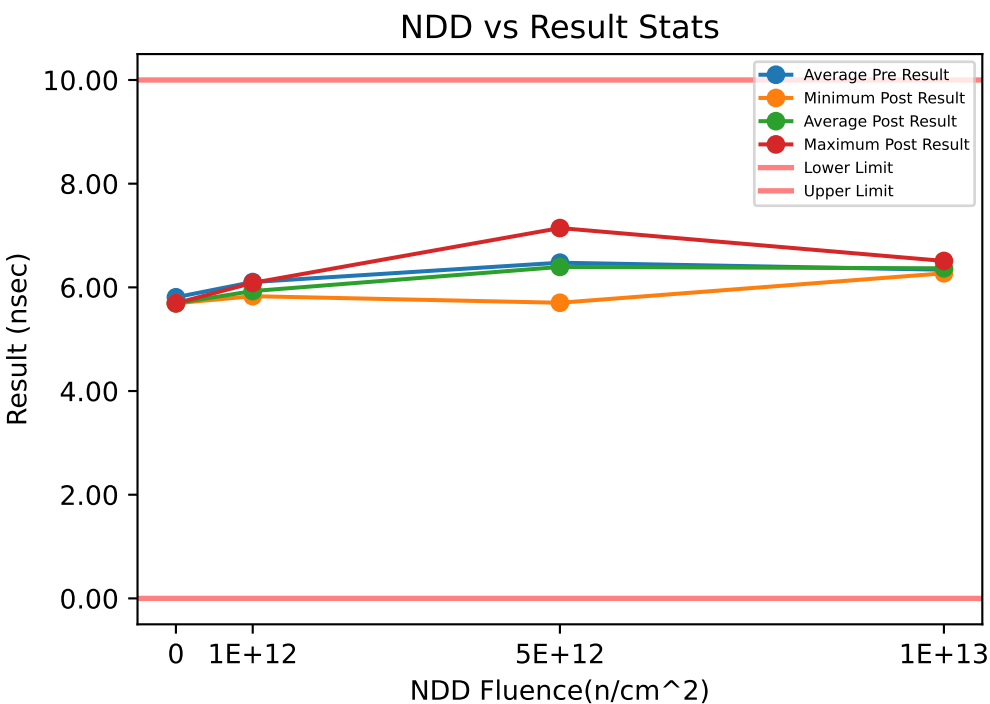
NDD vs Post - Pre Exposure Delta



Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	13.134	13.134	13.134		12.999	12.999	12.999		-0.1348	-0.1348	-0.1348	
1e+12	12.824	12.971	13.065	0.12921	12.552	12.717	12.81	0.14268	-0.2716	-0.25473	-0.2376	0.017002
5e+12	13.119	13.462	13.981	0.45693	13.093	13.292	13.67	0.32684	-0.3114	-0.1699	-0.0048	0.15466
1e+13	13.235	13.372	13.479	0.1246	13.13	13.281	13.422	0.14634	-0.1094	-0.0903	-0.0566	0.029272

Device Test: 97.10 T_RLH_MIN(DLH Dead Time Min 2MHz VIN_14V)



Test Results (Lower Limit = 0.0,
Upper Limit = 10.0 (nsec))

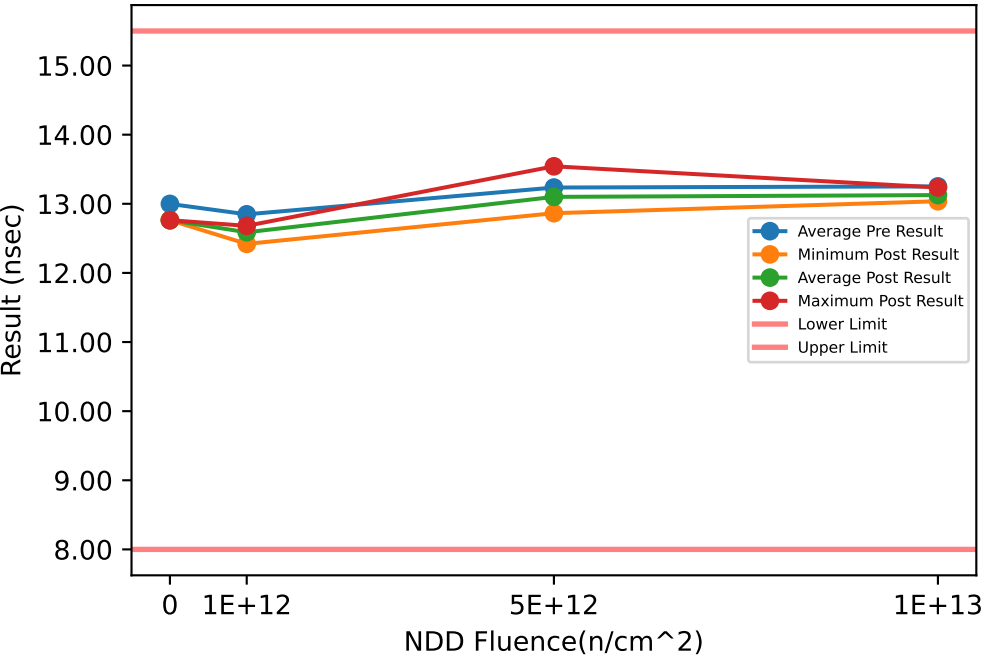
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	6.3212	6.0865	-0.2347
551	1e+12	NDD	6.0187	5.869	-0.1497
552	1e+12	NDD	5.9677	5.83	-0.1377
553	5e+12	NDD	6.3895	6.3347	-0.0548
554	5e+12	NDD	7.303	7.144	-0.159
555	5e+12	NDD	5.7347	5.7029	-0.0318
556	1e+13	NDD	6.5756	6.5092	-0.0664
557	1e+13	NDD	6.226	6.2713	0.0453
558	1e+13	NDD	6.2179	6.322	0.1041
559	0	NDD, Ctrl	5.8088	5.6934	-0.1154

Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.8088	5.8088	5.8088		5.6934	5.6934	5.6934		-0.1154	-0.1154	-0.1154	
1e+12	5.9677	6.1025	6.3212	0.19108	5.83	5.9285	6.0865	0.13821	-0.2347	-0.17403	-0.1377	0.05288
5e+12	5.7347	6.4757	7.303	0.7877	5.7029	6.3939	7.144	0.72237	-0.159	-0.081867	-0.0318	0.067782
1e+13	6.2179	6.3398	6.5756	0.20422	6.2713	6.3675	6.5092	0.12531	-0.0664	0.027667	0.1041	0.086607

Device Test: 97.11 T_RLH_SMALL(DLH Dead Time Small 2MHz VIN_14V)

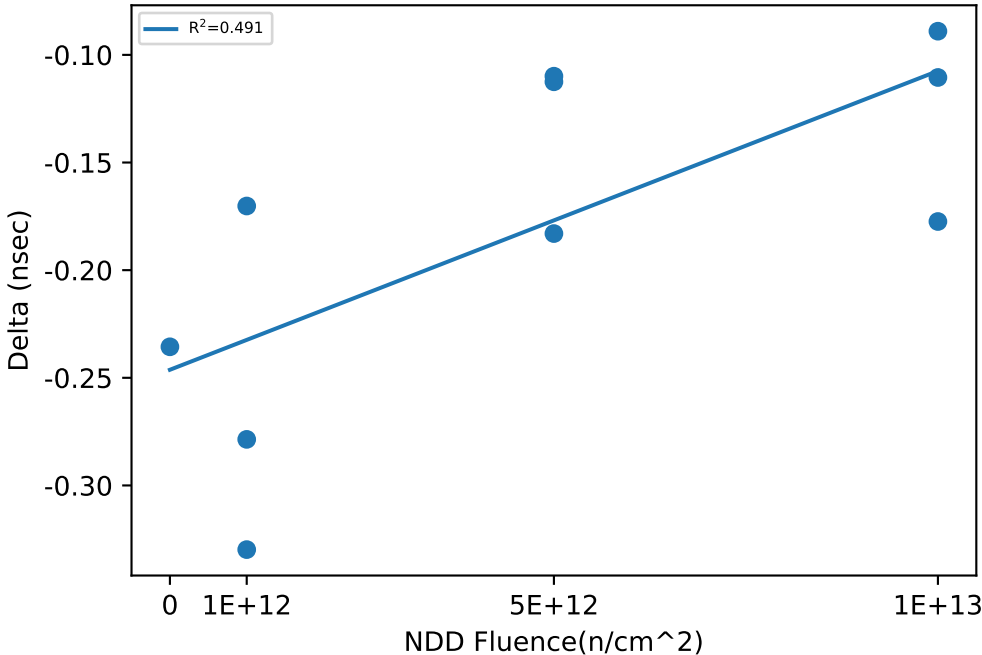
NDD vs Result Stats



Test Results (Lower Limit = 8.0, Upper Limit = 15.5 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	12.851	12.681	-0.1702
551	1e+12	NDD	12.699	12.42	-0.2786
552	1e+12	NDD	12.993	12.663	-0.3298
553	5e+12	NDD	13.047	12.864	-0.183
554	5e+12	NDD	13.655	13.542	-0.1125
555	5e+12	NDD	13.004	12.894	-0.1099
556	1e+13	NDD	13.214	13.037	-0.1774
557	1e+13	NDD	13.325	13.236	-0.089
558	1e+13	NDD	13.216	13.106	-0.1105
559	0	NDD, Ctrl	12.998	12.763	-0.2356

NDD vs Post - Pre Exposure Delta

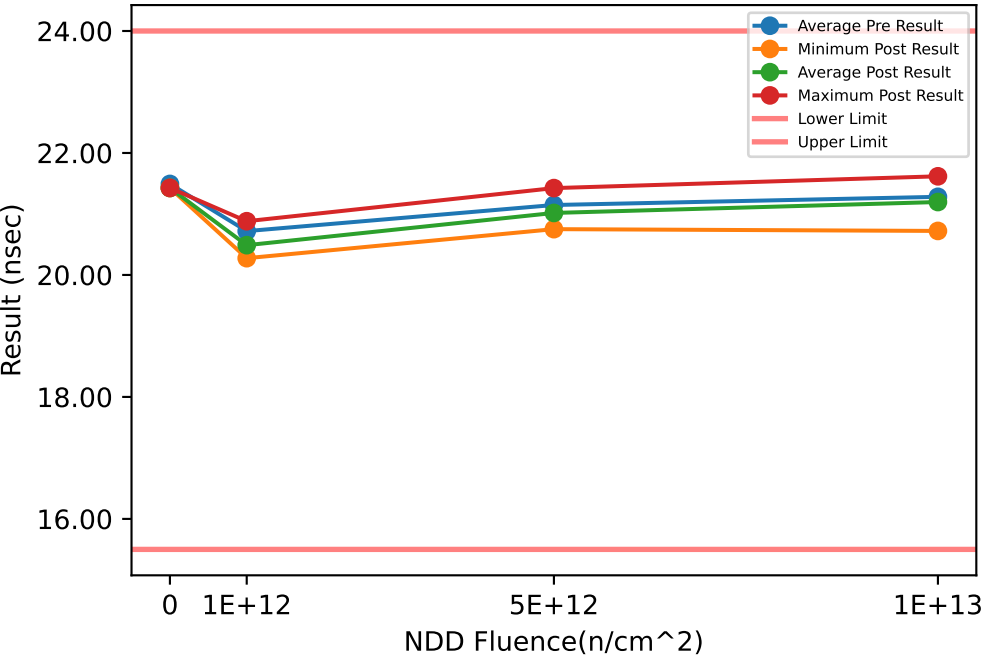


Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	12.998	12.998	12.998		12.763	12.763	12.763		-0.2356	-0.2356	-0.2356	
1e+12	12.699	12.848	12.993	0.14718	12.42	12.588	12.681	0.1458	-0.3298	-0.25953	-0.1702	0.08149
5e+12	13.004	13.235	13.655	0.36403	12.864	13.1	13.542	0.38328	-0.183	-0.13513	-0.1099	0.041474
1e+13	13.214	13.252	13.325	0.063112	13.037	13.126	13.236	0.10089	-0.1774	-0.12563	-0.089	0.046102

Device Test: 97.12 T_RLH_MID(DLH Dead Time Mid 2MHz VIN_14V)

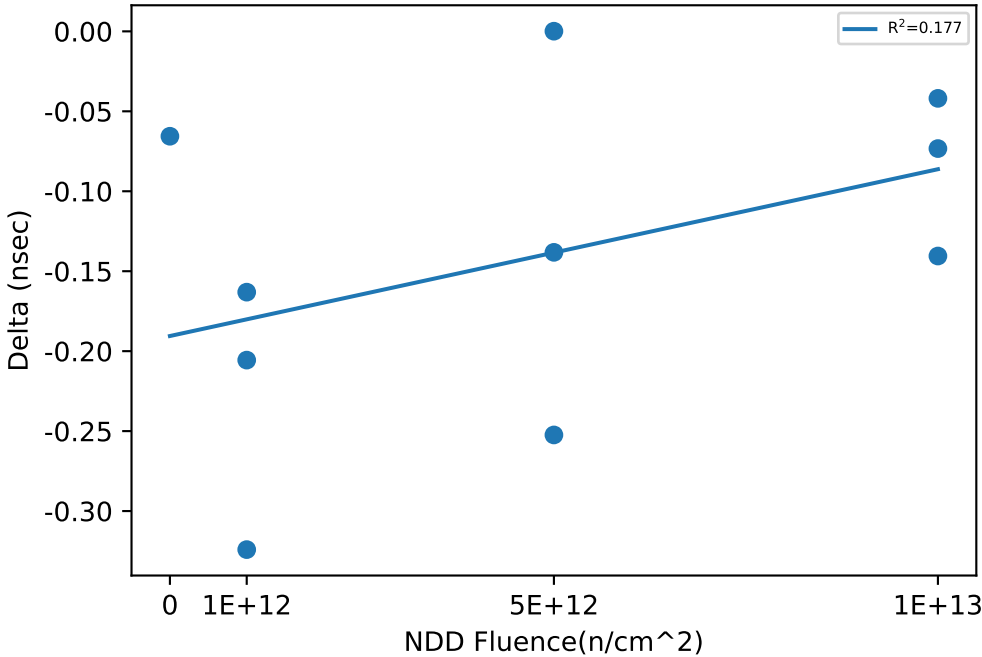
NDD vs Result Stats



Test Results (Lower Limit = 15.5, Upper Limit = 24.0 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	20.632	20.308	-0.3241
551	1e+12	NDD	20.481	20.275	-0.2056
552	1e+12	NDD	21.044	20.881	-0.1631
553	5e+12	NDD	20.889	20.751	-0.1382
554	5e+12	NDD	21.128	20.875	-0.2524
555	5e+12	NDD	21.424	21.424	0.0001
556	1e+13	NDD	20.795	20.722	-0.0733
557	1e+13	NDD	21.659	21.617	-0.0419
558	1e+13	NDD	21.388	21.248	-0.1405
559	0	NDD, Ctrl	21.492	21.427	-0.0656

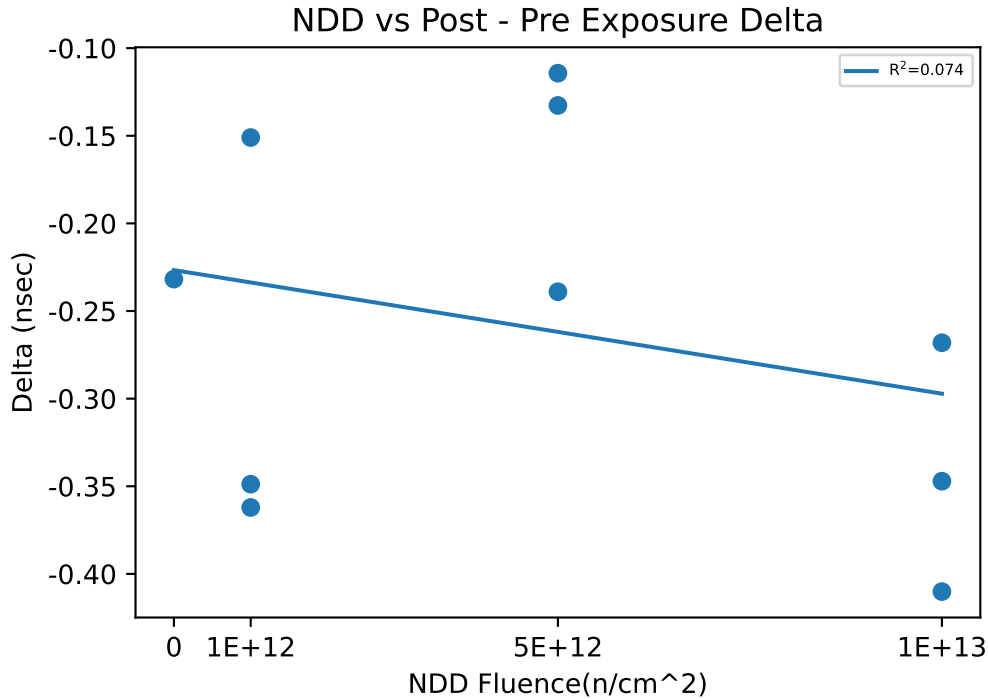
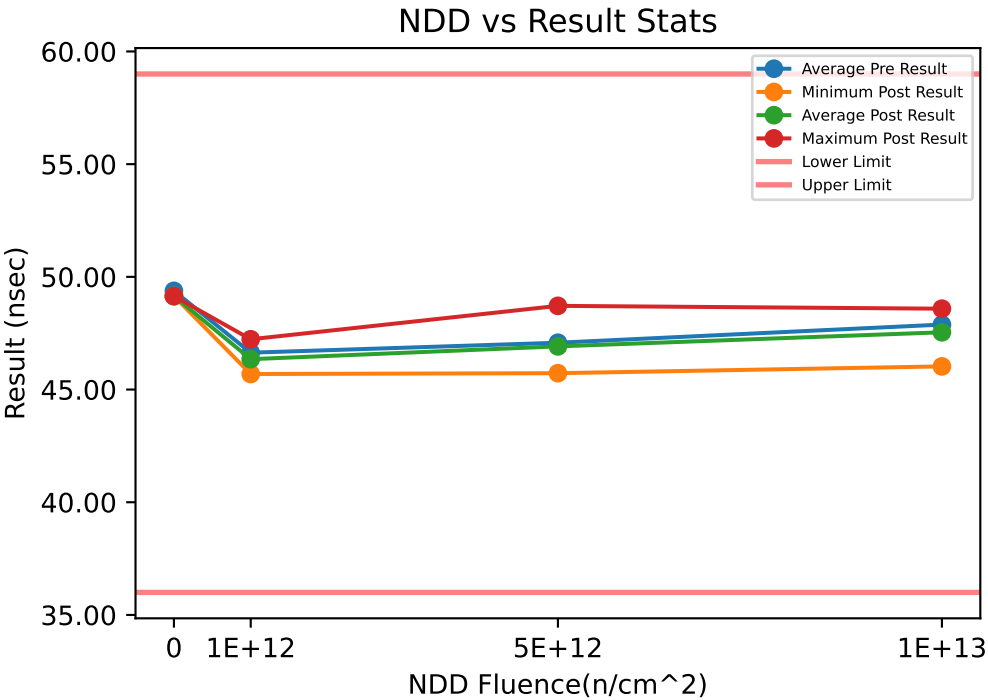
NDD vs Post - Pre Exposure Delta



Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	21.492	21.492	21.492		21.427	21.427	21.427		-0.0656	-0.0656	-0.0656	
1e+12	20.481	20.719	21.044	0.29158	20.275	20.488	20.881	0.34069	-0.3241	-0.23093	-0.1631	0.083436
5e+12	20.889	21.147	21.424	0.26788	20.751	21.017	21.424	0.35815	-0.2524	-0.13017	0.0001	0.12644
1e+13	20.795	21.281	21.659	0.442	20.722	21.196	21.617	0.45007	-0.1405	-0.085233	-0.0419	0.050372

Device Test: 97.13 T_RLH_LARGE(DLH Dead Time Large 2MHz VIN_14V)



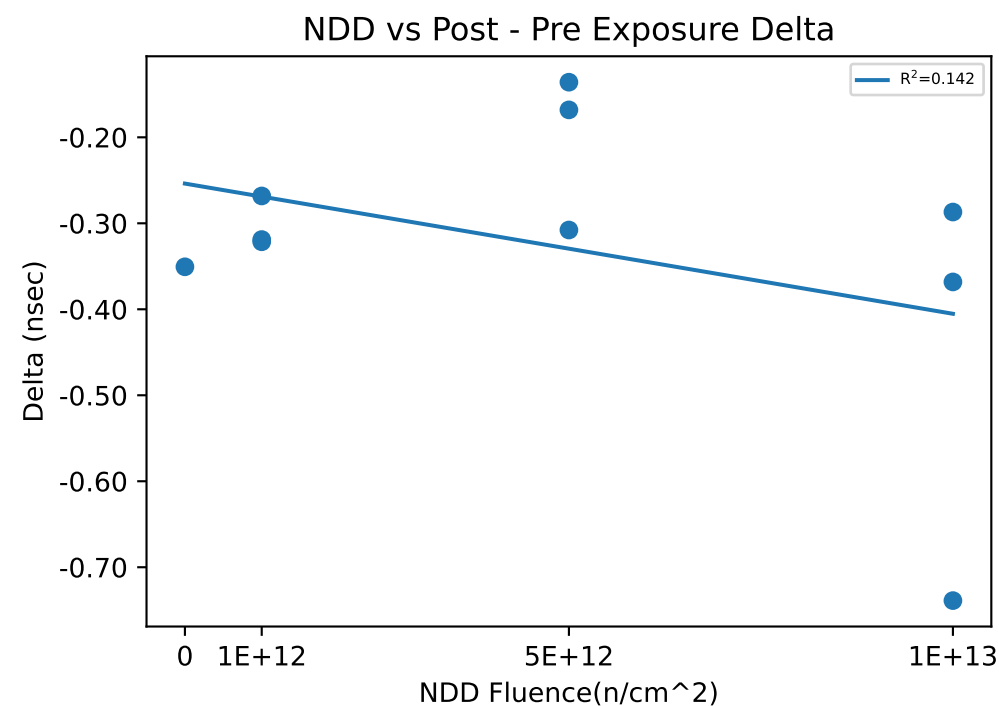
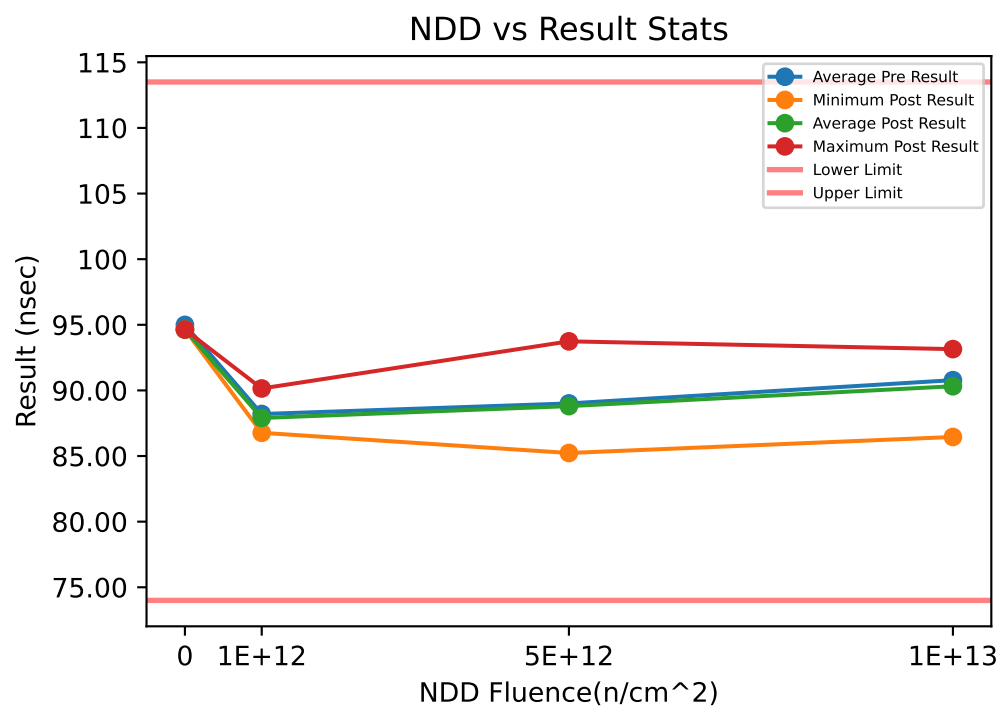
Test Results (Lower Limit = 36.0, Upper Limit = 59.0 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	46.274	46.123	-0.151
551	1e+12	NDD	46.051	45.689	-0.3621
552	1e+12	NDD	47.58	47.231	-0.3488
553	5e+12	NDD	46.42	46.306	-0.1143
554	5e+12	NDD	45.965	45.726	-0.239
555	5e+12	NDD	48.846	48.713	-0.1327
556	1e+13	NDD	46.295	46.027	-0.2681
557	1e+13	NDD	48.934	48.587	-0.3471
558	1e+13	NDD	48.417	48.007	-0.4101
559	0	NDD, Ctrl	49.379	49.147	-0.2318

Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	49.379	49.379	49.379		49.147	49.147	49.147		-0.2318	-0.2318	-0.2318	
1e+12	46.051	46.635	47.58	0.82577	45.689	46.348	47.231	0.79513	-0.3621	-0.2873	-0.151	0.11823
5e+12	45.965	47.077	48.846	1.5487	45.726	46.915	48.713	1.584	-0.239	-0.162	-0.1143	0.067316
1e+13	46.295	47.882	48.934	1.3987	46.027	47.54	48.587	1.3425	-0.4101	-0.34177	-0.2681	0.07115

Device Test: 97.14 T_RLH_MAX(DLH Dead Time Max 2MHz VIN_14V)



Test Results (Lower Limit = 74.0,
Upper Limit = 113.5 (nsec))

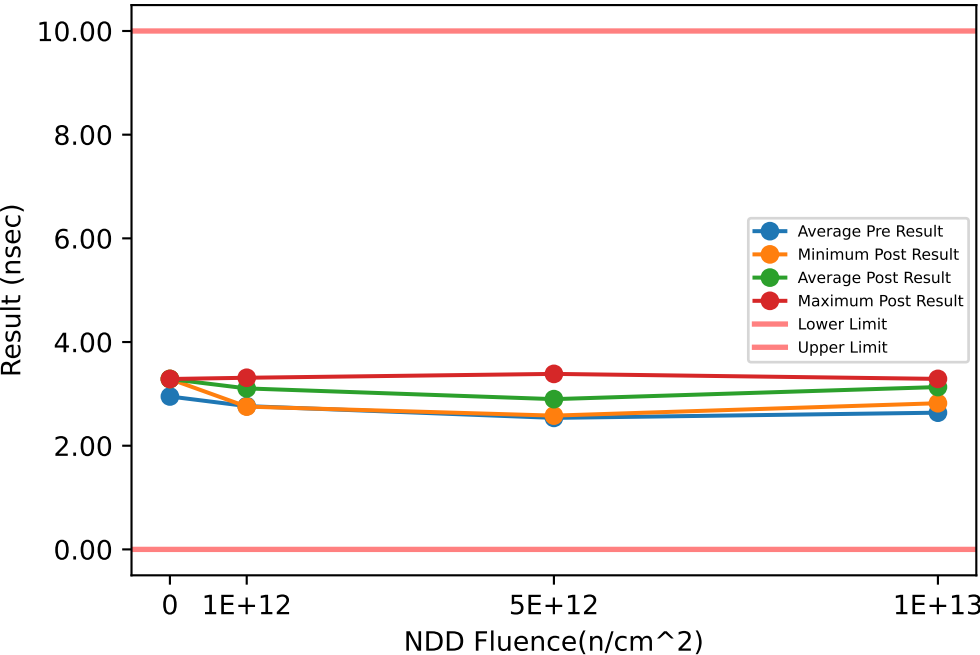
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	87.048	86.78	-0.2682
551	1e+12	NDD	87.089	86.77	-0.3189
552	1e+12	NDD	90.468	90.147	-0.3215
553	5e+12	NDD	87.607	87.439	-0.1681
554	5e+12	NDD	85.539	85.232	-0.3078
555	5e+12	NDD	93.875	93.739	-0.1359
556	1e+13	NDD	86.821	86.453	-0.3682
557	1e+13	NDD	93.433	93.147	-0.2869
558	1e+13	NDD	92.091	91.352	-0.7388
559	0	NDD, Ctrl	94.99	94.64	-0.3506

Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	94.99	94.99	94.99		94.64	94.64	94.64		-0.3506	-0.3506	-0.3506	
1e+12	87.048	88.202	90.468	1.9629	86.77	87.899	90.147	1.9467	-0.3215	-0.30287	-0.2682	0.03005
5e+12	85.539	89.007	93.875	4.3404	85.232	88.803	93.739	4.4146	-0.3078	-0.20393	-0.1359	0.091381
1e+13	86.821	90.782	93.433	3.4951	86.453	90.317	93.147	3.4647	-0.7388	-0.46463	-0.2869	0.24089

Device Test: 97.19 T_RHL_MIN(DHL Dead Time Min 500kHz VIN_14V)

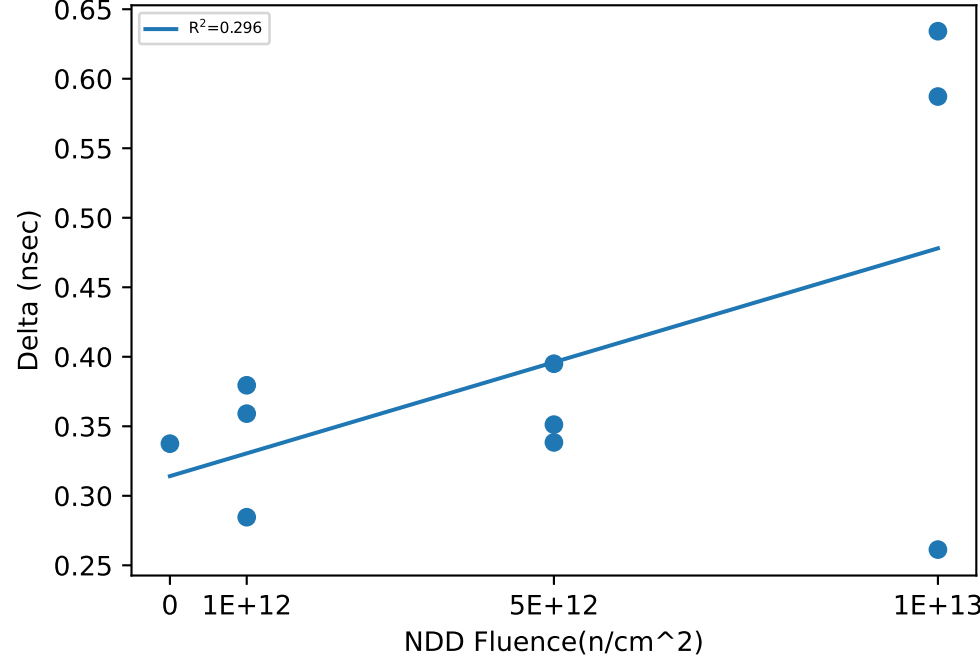
NDD vs Result Stats



Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	2.8922	3.2513	0.3591
551	1e+12	NDD	2.4696	2.7542	0.2846
552	1e+12	NDD	2.9313	3.3108	0.3795
553	5e+12	NDD	3.0343	3.3855	0.3512
554	5e+12	NDD	2.242	2.5804	0.3384
555	5e+12	NDD	2.3344	2.7294	0.395
556	1e+13	NDD	2.5583	2.8196	0.2613
557	1e+13	NDD	2.6516	3.2858	0.6342
558	1e+13	NDD	2.702	3.2892	0.5872
559	0	NDD, Ctrl	2.9497	3.2872	0.3375

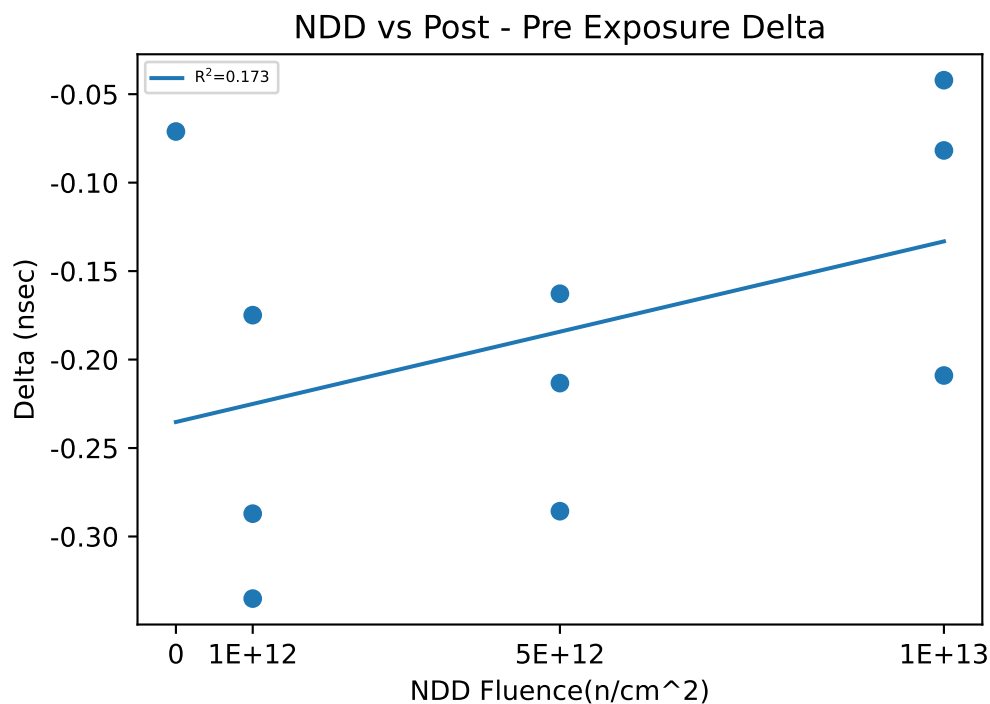
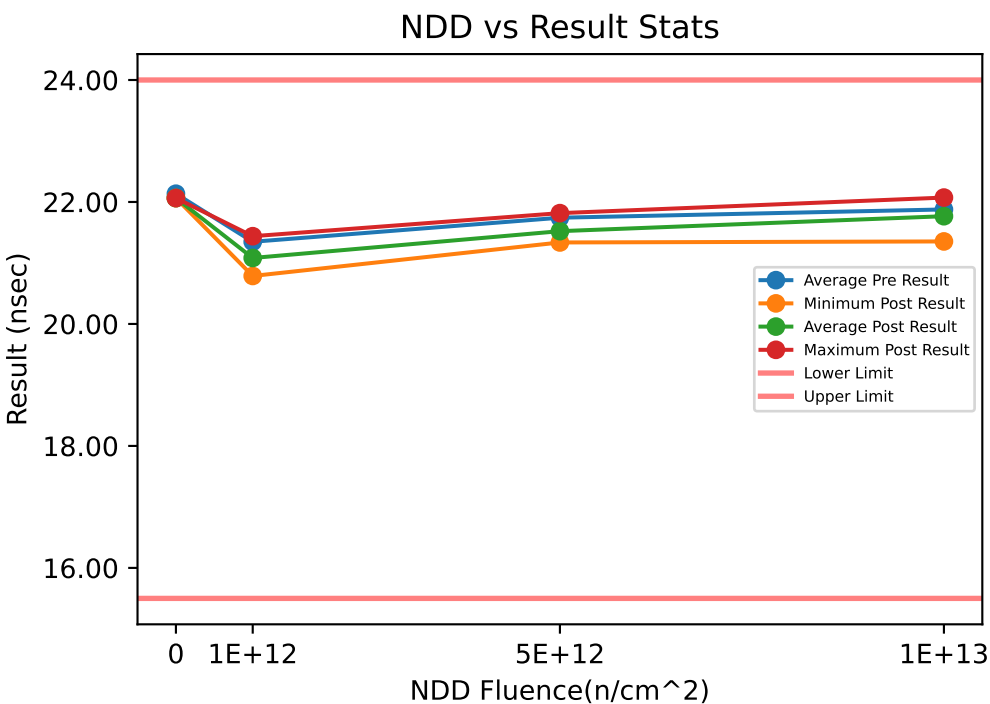
NDD vs Post - Pre Exposure Delta



Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.9497	2.9497	2.9497		3.2872	3.2872	3.2872		0.3375	0.3375	0.3375	
1e+12	2.4696	2.7644	2.9313	0.25602	2.7542	3.1054	3.3108	0.30563	0.2846	0.34107	0.3795	0.049954
5e+12	2.242	2.5369	3.0343	0.43323	2.5804	2.8984	3.3855	0.42834	0.3384	0.36153	0.395	0.029681
1e+13	2.5583	2.6373	2.702	0.072909	2.8196	3.1315	3.2892	0.27015	0.2613	0.49423	0.6342	0.20309

Device Test: 97.2 T_RLH_MID(DLH Dead Time Mid 500kHz VIN_14V)



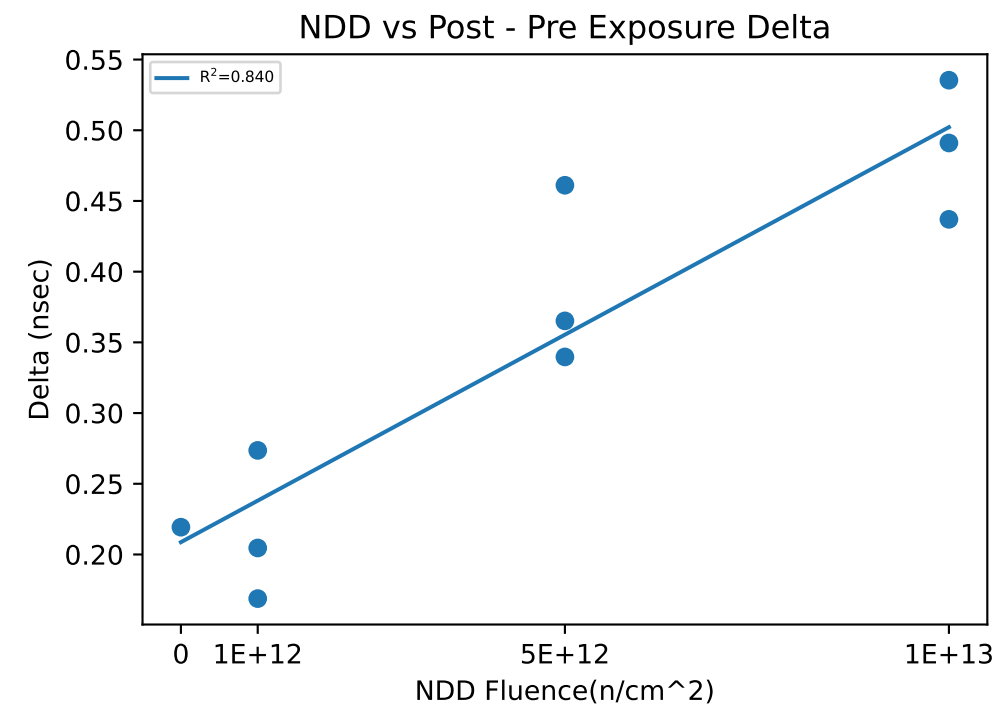
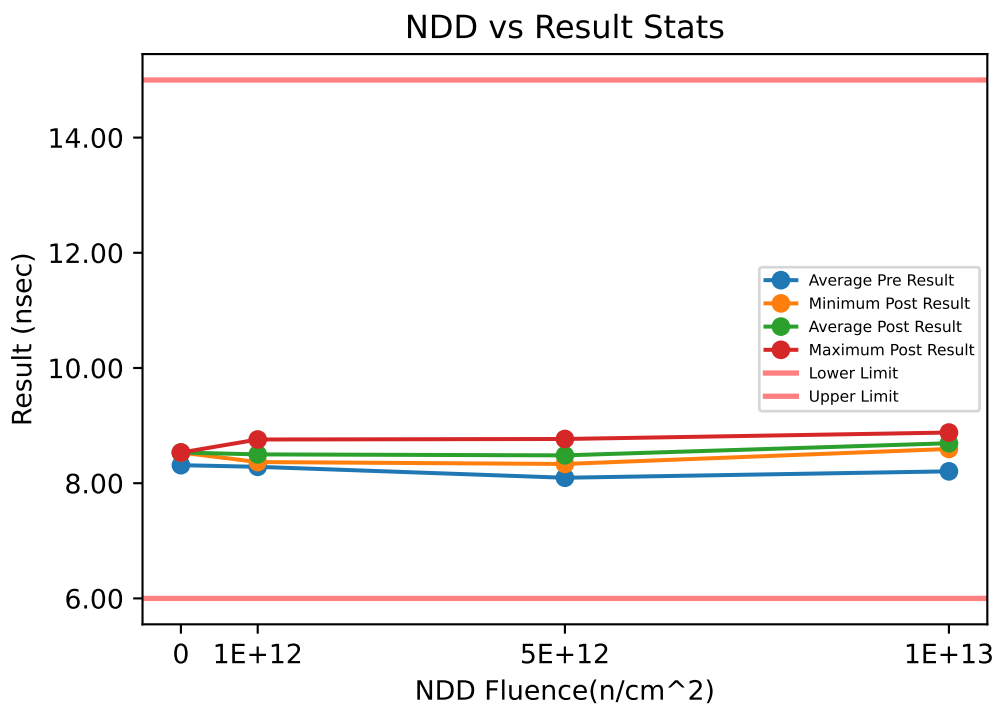
Test Results (Lower Limit = 15.5, Upper Limit = 24.0 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	21.307	21.02	-0.2871
551	1e+12	NDD	21.122	20.787	-0.3351
552	1e+12	NDD	21.614	21.439	-0.1749
553	5e+12	NDD	21.499	21.336	-0.1628
554	5e+12	NDD	21.696	21.411	-0.2857
555	5e+12	NDD	22.03	21.817	-0.2133
556	1e+13	NDD	21.435	21.353	-0.0818
557	1e+13	NDD	22.114	22.072	-0.0421
558	1e+13	NDD	22.084	21.875	-0.209
559	0	NDD, Ctrl	22.135	22.064	-0.0711

Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	22.135	22.135	22.135		22.064	22.064	22.064		-0.0711	-0.0711	-0.0711	
1e+12	21.122	21.348	21.614	0.24834	20.787	21.082	21.439	0.33033	-0.3351	-0.2657	-0.1749	0.082216
5e+12	21.499	21.742	22.03	0.26851	21.336	21.521	21.817	0.25874	-0.2857	-0.2206	-0.1628	0.061774
1e+13	21.435	21.878	22.114	0.38372	21.353	21.767	22.072	0.37152	-0.209	-0.11097	-0.0421	0.087189

Device Test: 97.20 T_RHL_SMALL(DHL Dead Time Small 500kHz VIN_14V)



Test Results (Lower Limit = 6.0, Upper Limit = 15.0 (nsec))

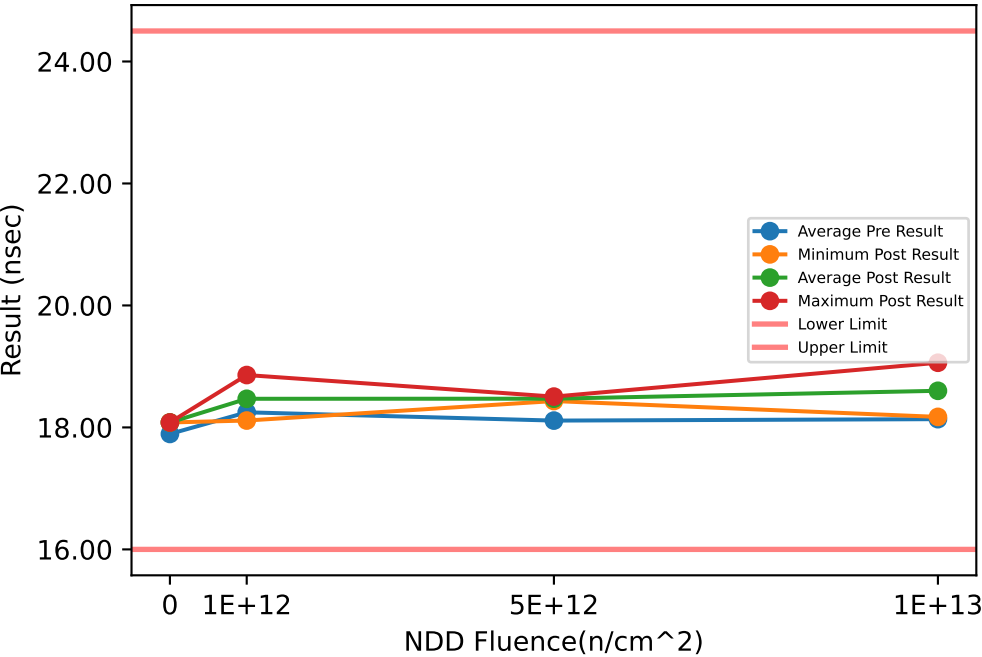
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	8.2061	8.3749	0.1688
551	1e+12	NDD	8.1624	8.367	0.2046
552	1e+12	NDD	8.485	8.7586	0.2736
553	5e+12	NDD	8.4023	8.7675	0.3652
554	5e+12	NDD	7.8871	8.3482	0.4611
555	5e+12	NDD	7.9941	8.3338	0.3397
556	1e+13	NDD	8.1158	8.6068	0.491
557	1e+13	NDD	8.4426	8.8796	0.437
558	1e+13	NDD	8.0593	8.5947	0.5354
559	0	NDD, Ctrl	8.3128	8.5321	0.2193

Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.3128	8.3128	8.3128		8.5321	8.5321	8.5321		0.2193	0.2193	0.2193	
1e+12	8.1624	8.2845	8.485	0.17501	8.367	8.5002	8.7586	0.22384	0.1688	0.21567	0.2736	0.053269
5e+12	7.8871	8.0945	8.4023	0.27188	8.3338	8.4832	8.7675	0.24635	0.3397	0.38867	0.4611	0.064012
1e+13	8.0593	8.2059	8.4426	0.20693	8.5947	8.6937	8.8796	0.16111	0.437	0.4878	0.5354	0.049278

Device Test: 97.21 T_RHL_MID(DHL Dead Time Mid 500kHz VIN_14V)

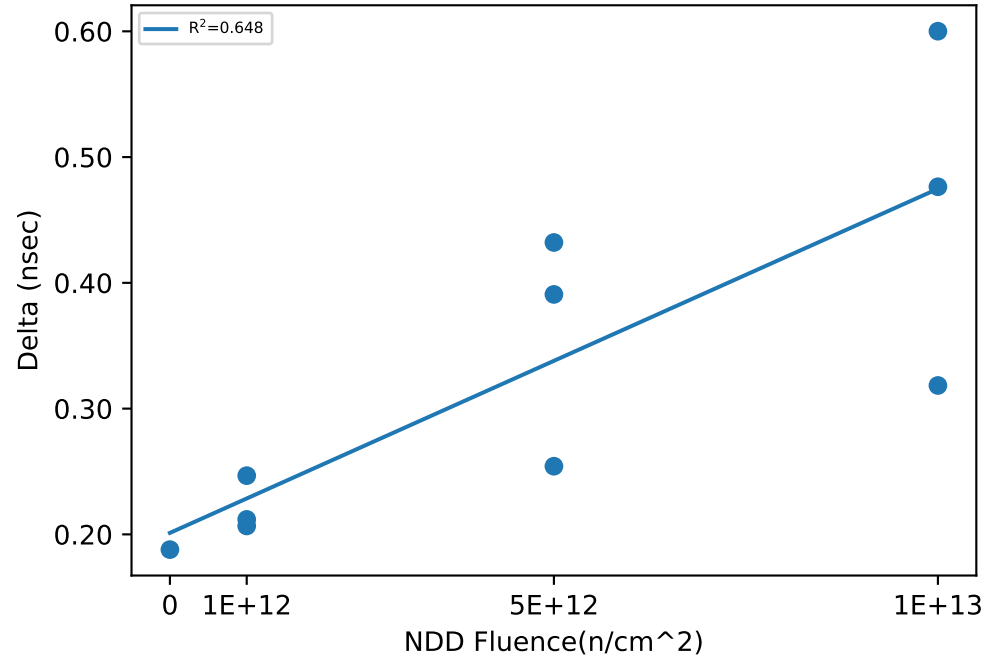
NDD vs Result Stats



Test Results (Lower Limit = 16.0, Upper Limit = 24.5 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	17.906	18.113	0.2067
551	1e+12	NDD	18.225	18.437	0.2119
552	1e+12	NDD	18.612	18.859	0.2467
553	5e+12	NDD	18.251	18.505	0.2542
554	5e+12	NDD	18.085	18.475	0.3908
555	5e+12	NDD	18	18.432	0.4321
556	1e+13	NDD	18.25	18.568	0.3184
557	1e+13	NDD	18.46	19.06	0.6001
558	1e+13	NDD	17.696	18.172	0.4764
559	0	NDD, Ctrl	17.893	18.081	0.1879

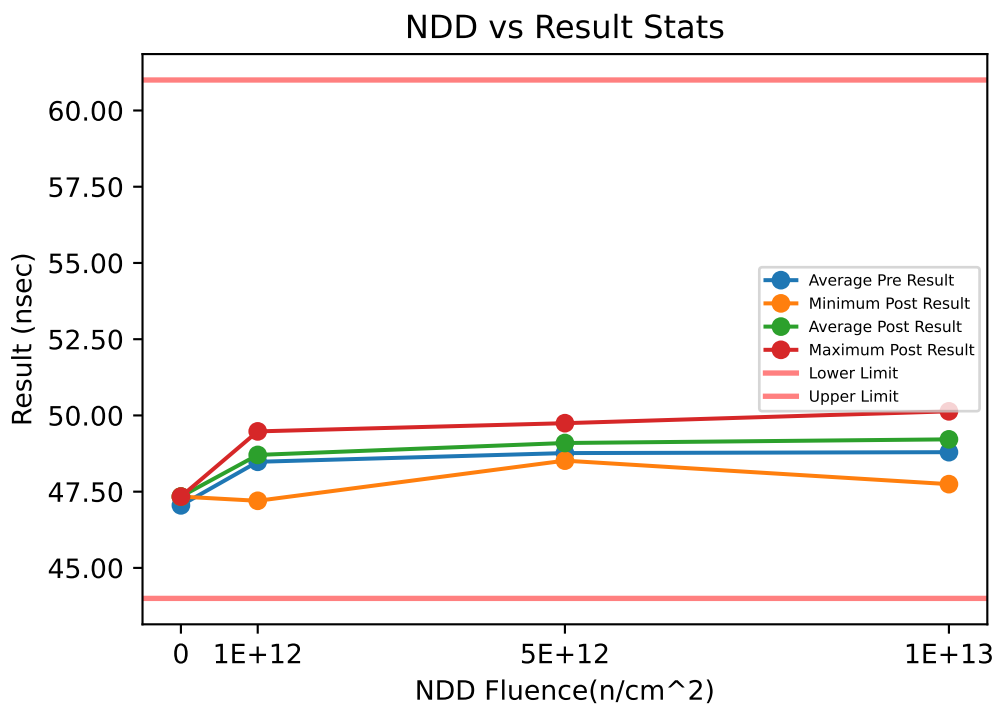
NDD vs Post - Pre Exposure Delta



Test Statistics (nsec)

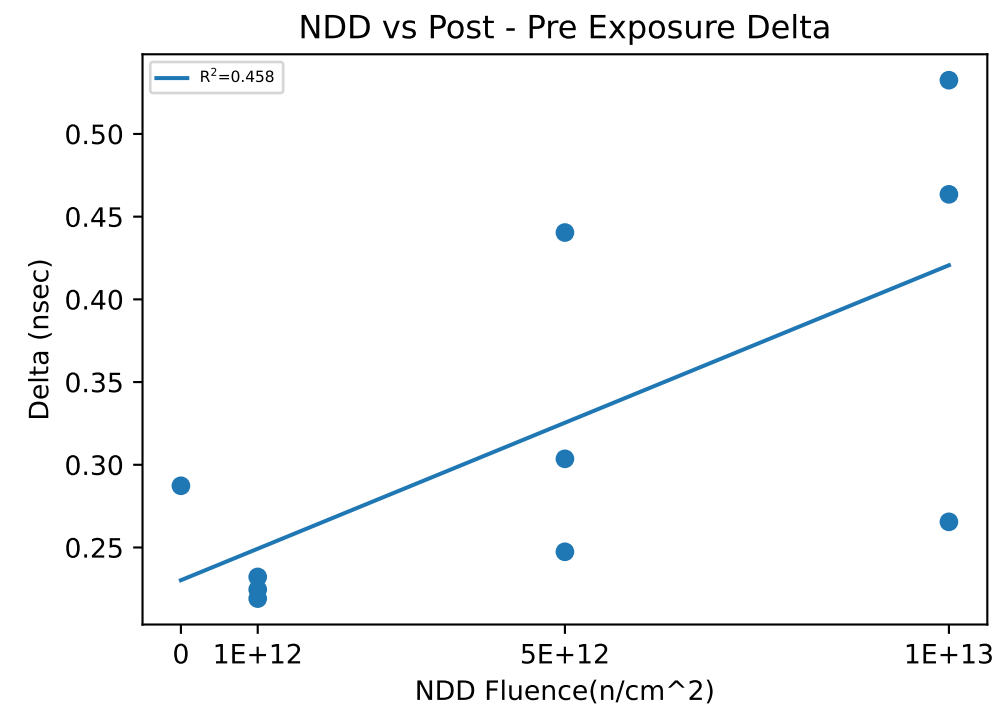
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	17.893	17.893	17.893		18.081	18.081	18.081		0.1879	0.1879	0.1879	
1e+12	17.906	18.248	18.612	0.35356	18.113	18.47	18.859	0.37408	0.2067	0.22177	0.2467	0.021749
5e+12	18	18.112	18.251	0.12772	18.432	18.471	18.505	0.036745	0.2542	0.35903	0.4321	0.093107
1e+13	17.696	18.135	18.46	0.39476	18.172	18.6	19.06	0.44482	0.3184	0.46497	0.6001	0.1412

Device Test: 97.22 T_RHL_LARGE(DHL Dead Time Large 500kHz VIN_14V)



Test Results (Lower Limit = 44.0, Upper Limit = 61.0 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	46.981	47.2	0.2191
551	1e+12	NDD	49.213	49.438	0.2246
552	1e+12	NDD	49.245	49.477	0.2322
553	5e+12	NDD	48.077	48.517	0.4404
554	5e+12	NDD	49.442	49.746	0.3036
555	5e+12	NDD	48.778	49.025	0.2474
556	1e+13	NDD	49.5	49.766	0.2655
557	1e+13	NDD	49.671	50.135	0.4635
558	1e+13	NDD	47.214	47.746	0.5325
559	0	NDD, Ctrl	47.051	47.338	0.2873

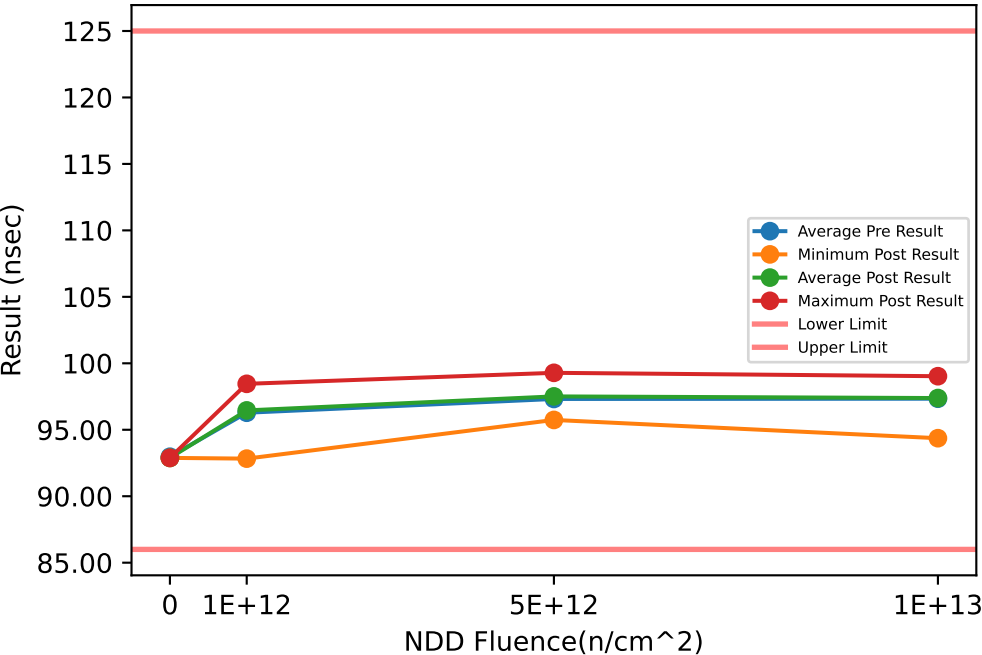


Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	47.051	47.051	47.051		47.338	47.338	47.338		0.2873	0.2873	0.2873	
1e+12	46.981	48.48	49.245	1.2976	47.2	48.705	49.477	1.303	0.2191	0.2253	0.2322	0.006578
5e+12	48.077	48.766	49.442	0.68258	48.517	49.096	49.746	0.61716	0.2474	0.33047	0.4404	0.099265
1e+13	47.214	48.795	49.671	1.3719	47.746	49.216	50.135	1.2856	0.2655	0.4205	0.5325	0.1386

Device Test: 97.23 T_RHL_MAX(DHL Dead Time Max 500kHz VIN_14V)

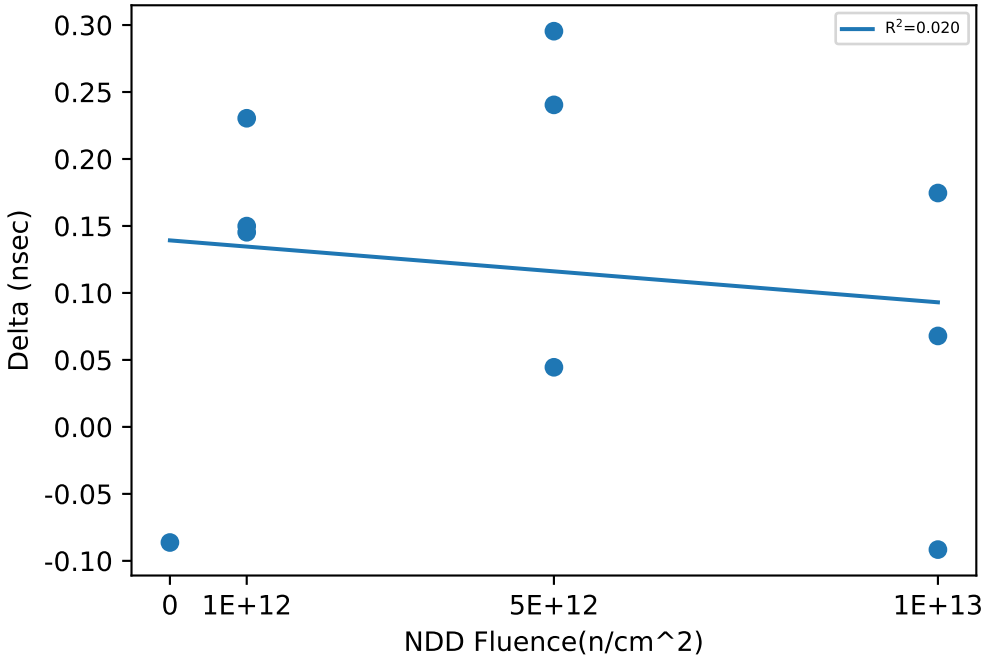
NDD vs Result Stats



Test Results (Lower Limit = 86.0, Upper Limit = 125.0 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	92.683	92.829	0.1453
551	1e+12	NDD	97.935	98.085	0.1499
552	1e+12	NDD	98.226	98.456	0.2304
553	5e+12	NDD	95.695	95.739	0.0445
554	5e+12	NDD	99.043	99.284	0.2404
555	5e+12	NDD	97.214	97.509	0.2954
556	1e+13	NDD	98.856	98.765	-0.0916
557	1e+13	NDD	98.855	99.029	0.1746
558	1e+13	NDD	94.298	94.366	0.0679
559	0	NDD, Ctrl	92.971	92.885	-0.0863

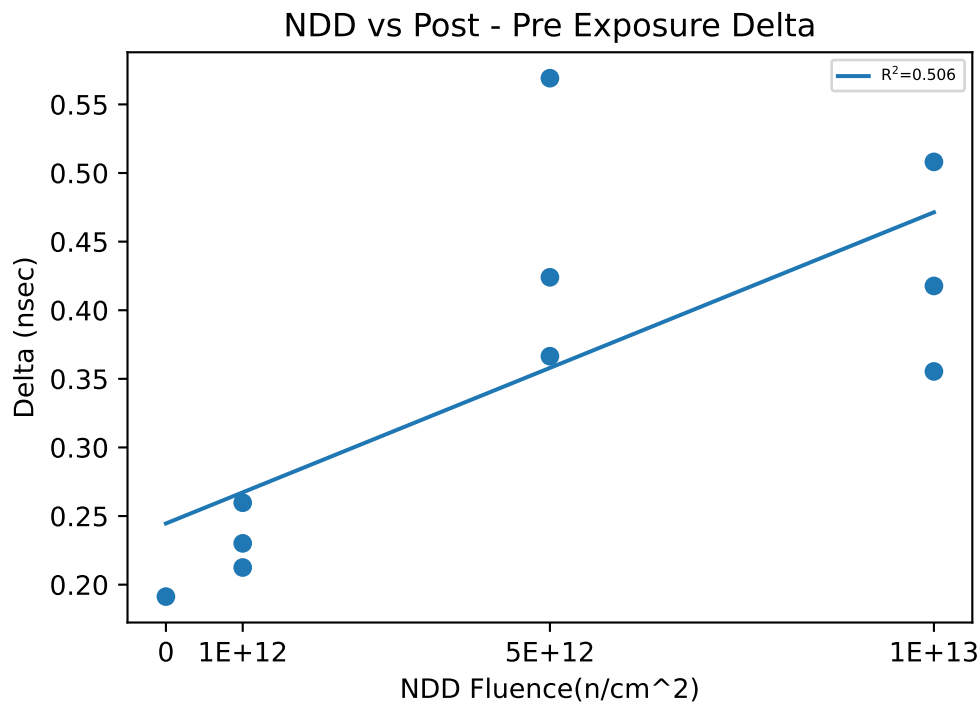
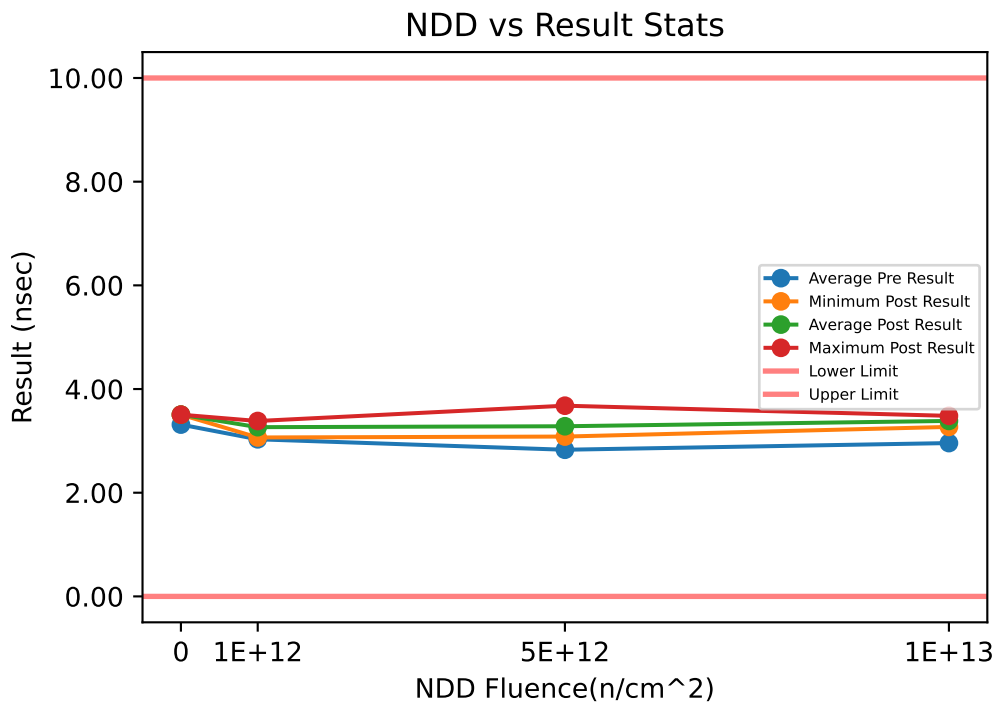
NDD vs Post - Pre Exposure Delta



Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	92.971	92.971	92.971		92.885	92.885	92.885		-0.0863	-0.0863	-0.0863	
1e+12	92.683	96.281	98.226	3.1194	92.829	96.456	98.456	3.1473	0.1453	0.1752	0.2304	0.04786
5e+12	95.695	97.317	99.043	1.6765	95.739	97.511	99.284	1.7721	0.0445	0.19343	0.2954	0.13188
1e+13	94.298	97.336	98.856	2.6312	94.366	97.387	99.029	2.6193	-0.0916	0.0503	0.1746	0.13397

Device Test: 97.24 T_RHL_MIN(DHL Dead Time Min 1MHz VIN_14V)



Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (nsec))

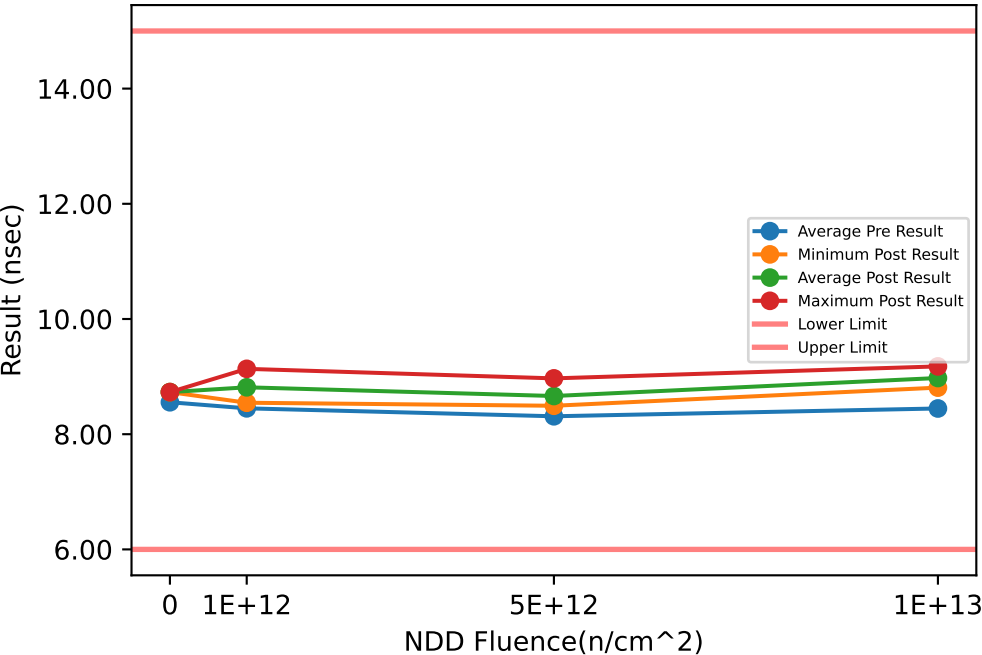
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	3.1143	3.3444	0.2301
551	1e+12	NDD	2.8062	3.0659	0.2597
552	1e+12	NDD	3.1709	3.3834	0.2125
553	5e+12	NDD	3.3121	3.6786	0.3665
554	5e+12	NDD	2.5142	3.0833	0.5691
555	5e+12	NDD	2.6605	3.0845	0.424
556	1e+13	NDD	2.914	3.2694	0.3554
557	1e+13	NDD	2.8939	3.402	0.5081
558	1e+13	NDD	3.0652	3.4829	0.4177
559	0	NDD, Ctrl	3.3143	3.5056	0.1913

Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.3143	3.3143	3.3143		3.5056	3.5056	3.5056		0.1913	0.1913	0.1913	
1e+12	2.8062	3.0305	3.1709	0.19627	3.0659	3.2646	3.3834	0.17315	0.2125	0.2341	0.2597	0.023853
5e+12	2.5142	2.8289	3.3121	0.42478	3.0833	3.2821	3.6786	0.34335	0.3665	0.4532	0.5691	0.10441
1e+13	2.8939	2.9577	3.0652	0.093639	3.2694	3.3848	3.4829	0.10779	0.3554	0.42707	0.5081	0.07678

Device Test: 97.25 T_RHL_SMALL(DHL Dead Time Small 1MHz VIN_14V)

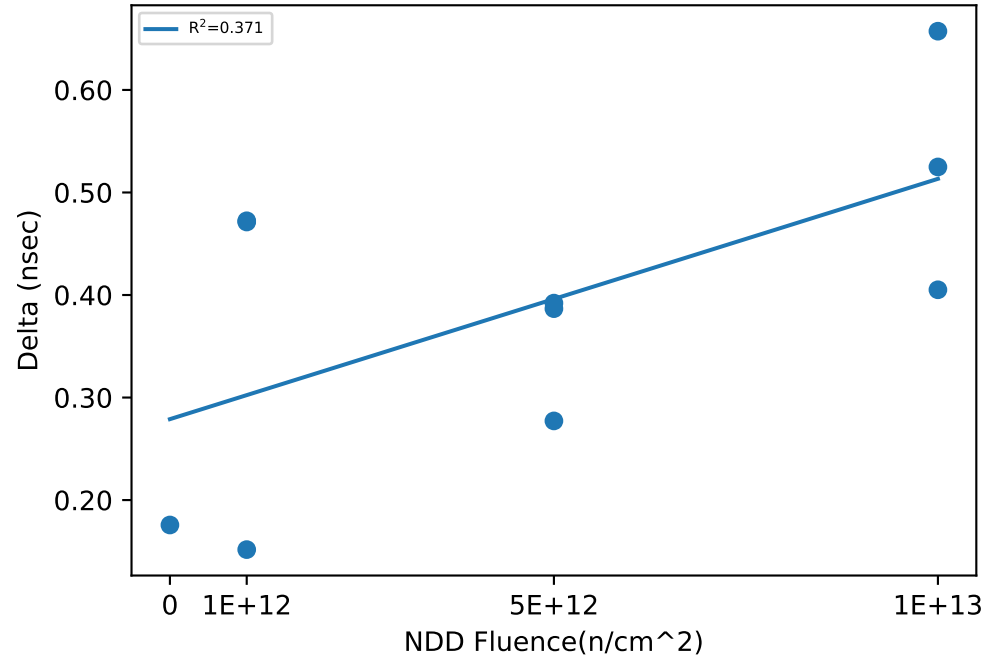
NDD vs Result Stats



Test Results (Lower Limit = 6.0, Upper Limit = 15.0 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	8.2906	8.7618	0.4712
551	1e+12	NDD	8.3944	8.5461	0.1517
552	1e+12	NDD	8.6622	9.1346	0.4724
553	5e+12	NDD	8.577	8.9691	0.3921
554	5e+12	NDD	8.2165	8.4937	0.2772
555	5e+12	NDD	8.1396	8.5263	0.3867
556	1e+13	NDD	8.4034	8.8085	0.4051
557	1e+13	NDD	8.6521	9.177	0.5249
558	1e+13	NDD	8.284	8.9413	0.6573
559	0	NDD, Ctrl	8.5547	8.7304	0.1757

NDD vs Post - Pre Exposure Delta

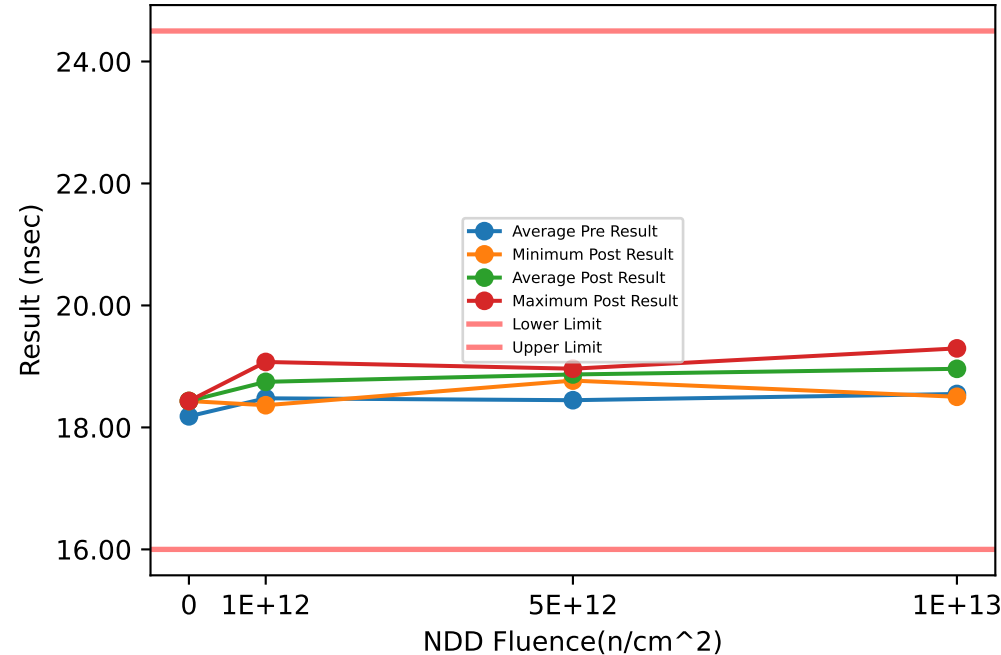


Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.5547	8.5547	8.5547		8.7304	8.7304	8.7304		0.1757	0.1757	0.1757	
1e+12	8.2906	8.4491	8.6622	0.19174	8.5461	8.8142	9.1346	0.29772	0.1517	0.3651	0.4724	0.18481
5e+12	8.1396	8.311	8.577	0.23352	8.4937	8.663	8.9691	0.26556	0.2772	0.352	0.3921	0.064835
1e+13	8.284	8.4465	8.6521	0.1878	8.8085	8.9756	9.177	0.18663	0.4051	0.5291	0.6573	0.12615

Device Test: 97.26 T_RHL_MID(DHL Dead Time Mid 1MHz VIN_14V)

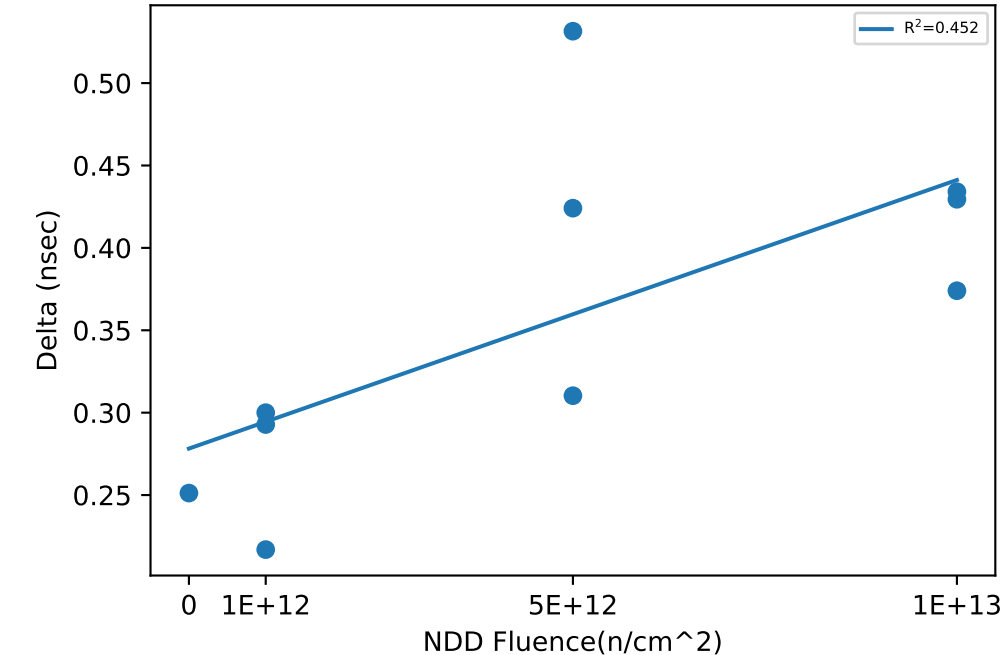
NDD vs Result Stats



Test Results (Lower Limit = 16.0, Upper Limit = 24.5 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	18.147	18.364	0.2169
551	1e+12	NDD	18.505	18.805	0.3
552	1e+12	NDD	18.781	19.073	0.2928
553	5e+12	NDD	18.564	18.875	0.3103
554	5e+12	NDD	18.431	18.963	0.5315
555	5e+12	NDD	18.343	18.768	0.4241
556	1e+13	NDD	18.655	19.084	0.4295
557	1e+13	NDD	18.862	19.296	0.4341
558	1e+13	NDD	18.128	18.502	0.374
559	0	NDD, Ctrl	18.182	18.433	0.2512

NDD vs Post - Pre Exposure Delta

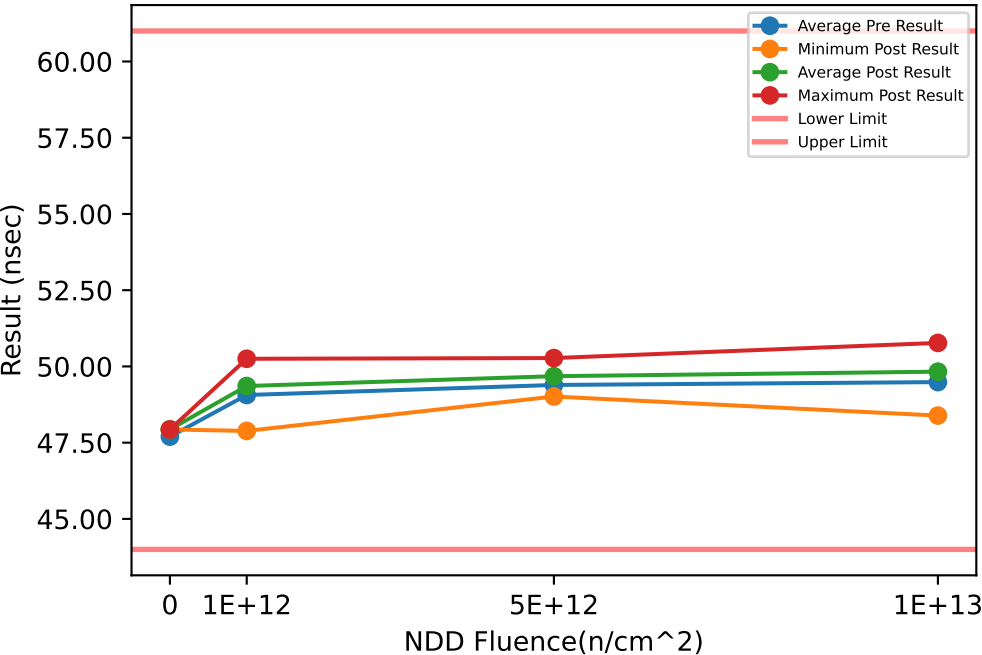


Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	18.182	18.182	18.182		18.433	18.433	18.433		0.2512	0.2512	0.2512	
1e+12	18.147	18.478	18.781	0.31764	18.364	18.747	19.073	0.35817	0.2169	0.2699	0.3	0.04604
5e+12	18.343	18.446	18.564	0.11112	18.768	18.868	18.963	0.097748	0.3103	0.42197	0.5315	0.11062
1e+13	18.128	18.548	18.862	0.37811	18.502	18.961	19.296	0.4109	0.374	0.41253	0.4341	0.03345

Device Test: 97.27 T_RHL_LARGE(DHL Dead Time Large 1MHz VIN_14V)

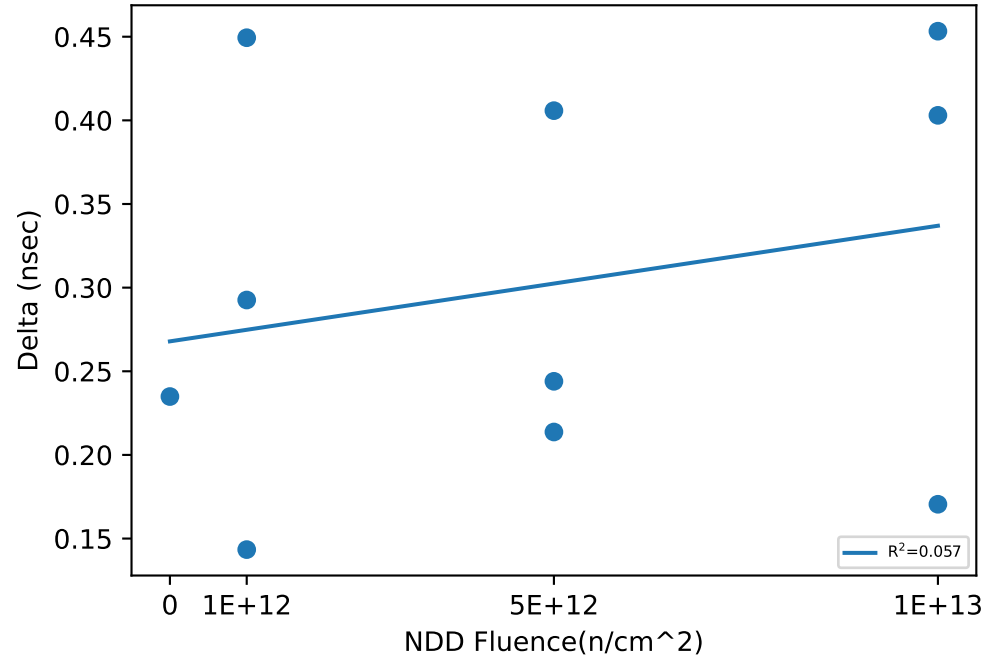
NDD vs Result Stats



Test Results (Lower Limit = 44.0, Upper Limit = 61.0 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	47.593	47.885	0.2926
551	1e+12	NDD	49.794	49.937	0.1434
552	1e+12	NDD	49.802	50.251	0.4494
553	5e+12	NDD	48.8	49.014	0.2137
554	5e+12	NDD	50.031	50.275	0.244
555	5e+12	NDD	49.346	49.751	0.4058
556	1e+13	NDD	50.155	50.325	0.1705
557	1e+13	NDD	50.318	50.771	0.4533
558	1e+13	NDD	47.986	48.389	0.403
559	0	NDD, Ctrl	47.698	47.933	0.2349

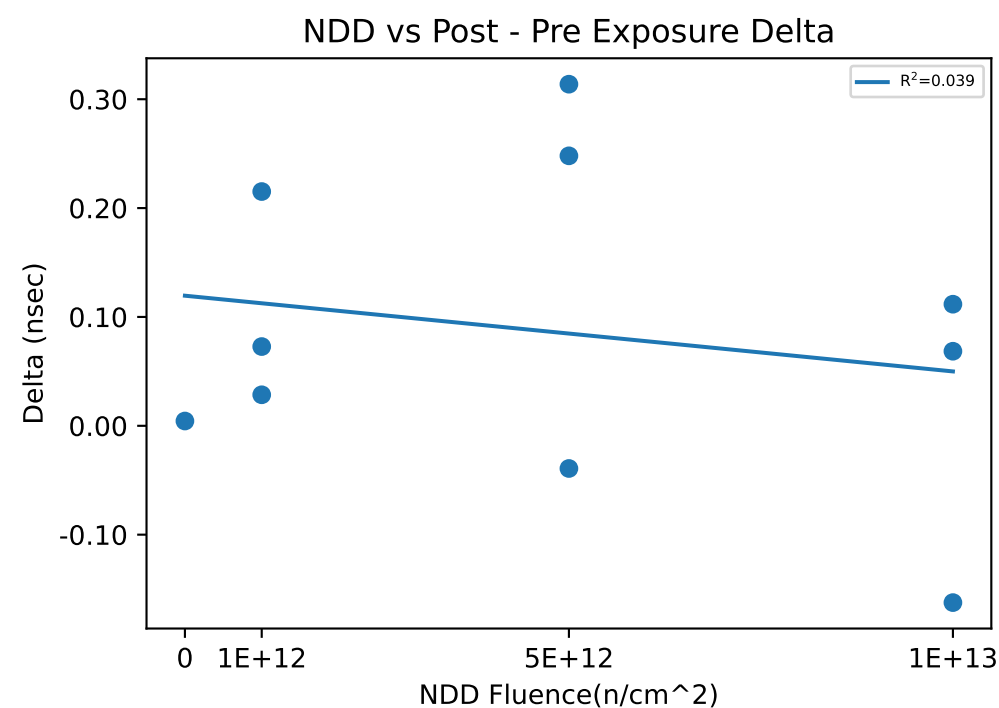
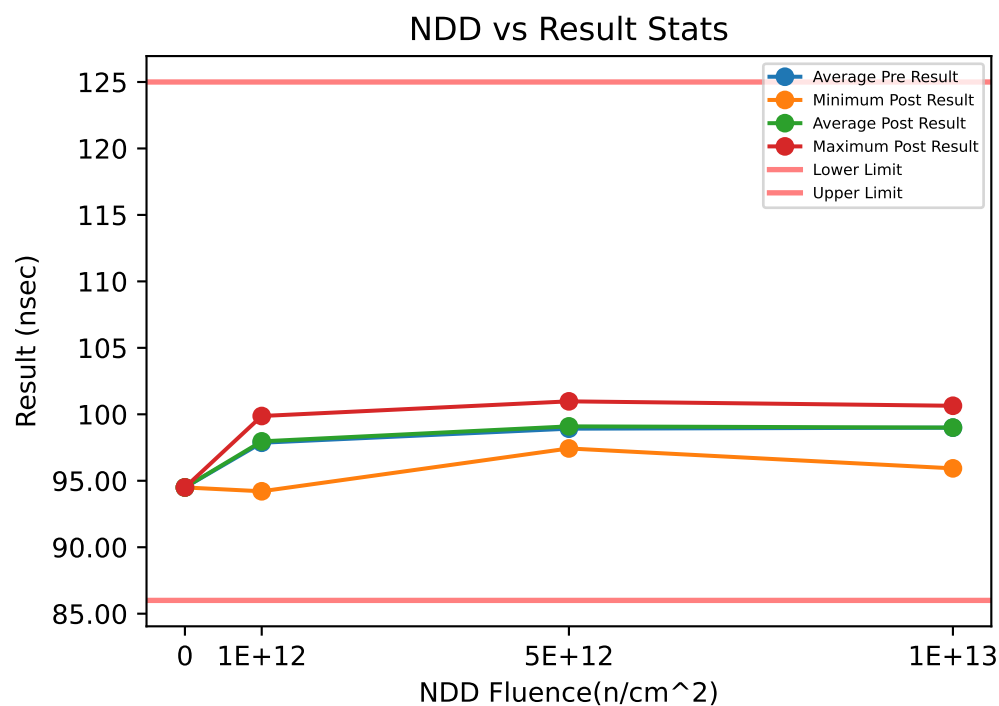
NDD vs Post - Pre Exposure Delta



Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	47.698	47.698	47.698		47.933	47.933	47.933		0.2349	0.2349	0.2349	
1e+12	47.593	49.063	49.802	1.2732	47.885	49.358	50.251	1.285	0.1434	0.29513	0.4494	0.15302
5e+12	48.8	49.392	50.031	0.61661	49.014	49.68	50.275	0.63348	0.2137	0.28783	0.4058	0.10328
1e+13	47.986	49.486	50.318	1.3022	48.389	49.828	50.771	1.2668	0.1705	0.34227	0.4533	0.15087

Device Test: 97.28 T_RHL_MAX(DHL Dead Time Max 1MHz VIN_14V)



Test Results (Lower Limit = 86.0, Upper Limit = 125.0 (nsec))

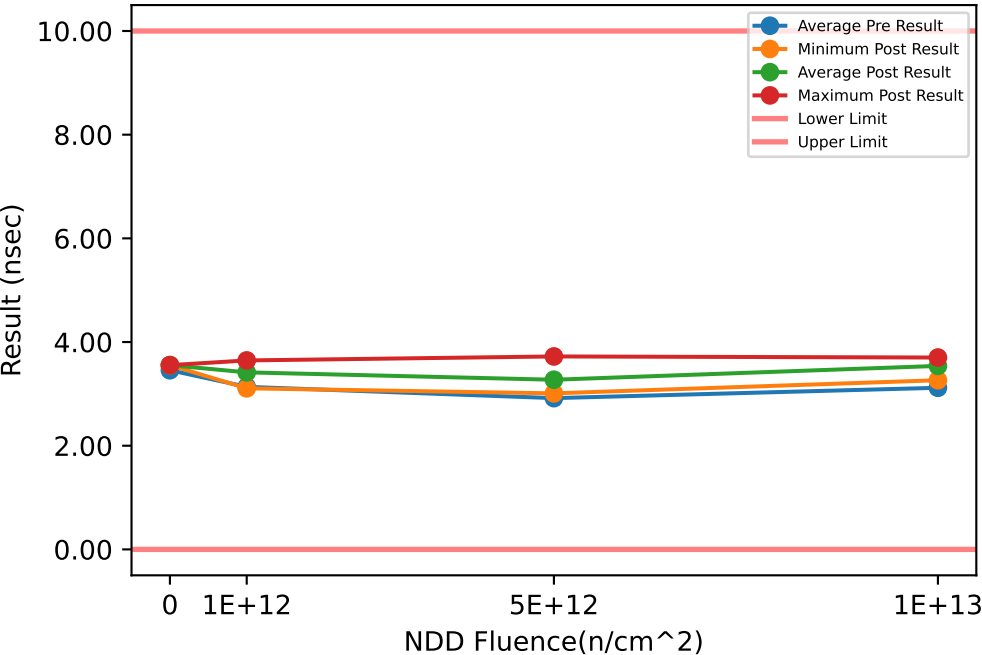
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	94.18	94.208	0.0285
551	1e+12	NDD	99.599	99.814	0.2152
552	1e+12	NDD	99.799	99.872	0.0728
553	5e+12	NDD	97.183	97.431	0.248
554	5e+12	NDD	100.66	100.97	0.3138
555	5e+12	NDD	98.912	98.873	-0.0392
556	1e+13	NDD	100.59	100.43	-0.1624
557	1e+13	NDD	100.57	100.64	0.0685
558	1e+13	NDD	95.822	95.934	0.1117
559	0	NDD, Ctrl	94.494	94.498	0.0044

Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	94.494	94.494	94.494		94.498	94.498	94.498		0.0044	0.0044	0.0044	
1e+12	94.18	97.859	99.799	3.1881	94.208	97.965	99.872	3.2533	0.0285	0.1055	0.2152	0.097551
5e+12	97.183	98.919	100.66	1.7391	97.431	99.093	100.97	1.7822	-0.0392	0.1742	0.3138	0.18772
1e+13	95.822	98.995	100.59	2.7478	95.934	99.001	100.64	2.6584	-0.1624	0.0059333	0.1117	0.14737

Device Test: 97.29 T_RHL_MIN(DHL Dead Time Min 2MHz VIN_14V)

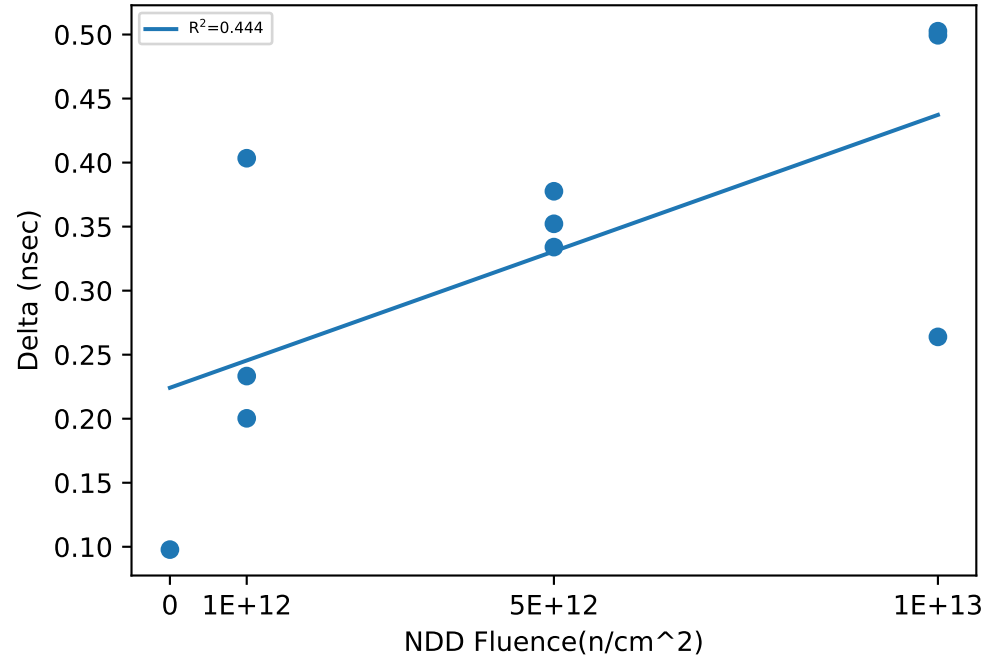
NDD vs Result Stats



Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	3.2418	3.6452	0.4034
551	1e+12	NDD	2.9068	3.1071	0.2003
552	1e+12	NDD	3.2594	3.4927	0.2333
553	5e+12	NDD	3.3445	3.7221	0.3776
554	5e+12	NDD	2.6762	3.0102	0.334
555	5e+12	NDD	2.7335	3.0857	0.3522
556	1e+13	NDD	2.9994	3.2633	0.2639
557	1e+13	NDD	3.2019	3.7013	0.4994
558	1e+13	NDD	3.1516	3.6542	0.5026
559	0	NDD, Ctrl	3.4561	3.5539	0.0978

NDD vs Post - Pre Exposure Delta

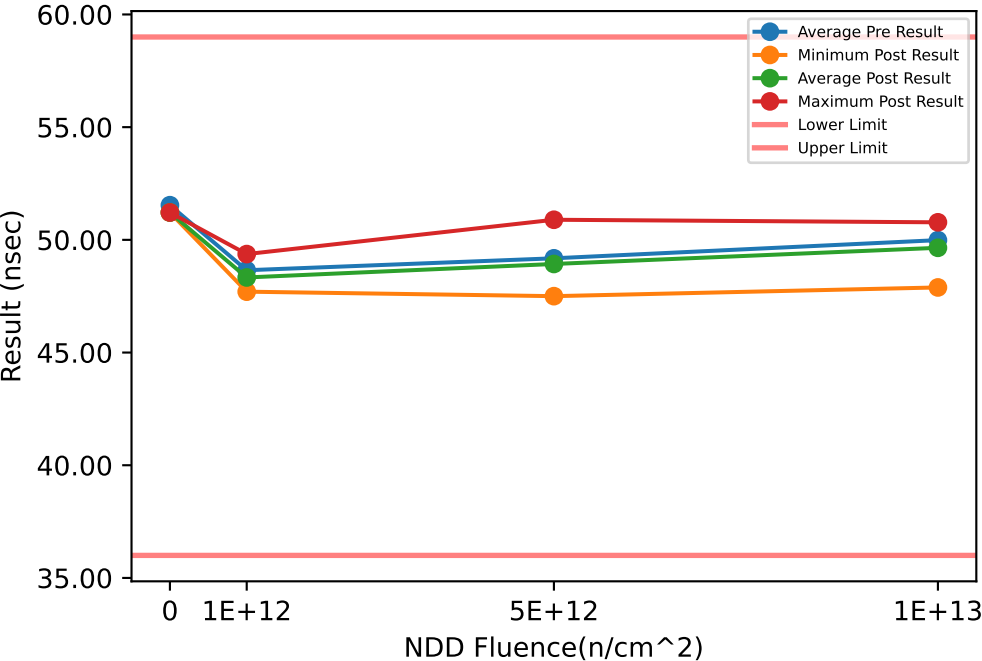


Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.4561	3.4561	3.4561		3.5539	3.5539	3.5539		0.0978	0.0978	0.0978	
1e+12	2.9068	3.136	3.2594	0.19869	3.1071	3.415	3.6452	0.27734	0.2003	0.279	0.4034	0.10899
5e+12	2.6762	2.9181	3.3445	0.37041	3.0102	3.2727	3.7221	0.39105	0.334	0.3546	0.3776	0.021899
1e+13	2.9994	3.1176	3.2019	0.10544	3.2633	3.5396	3.7013	0.24044	0.2639	0.42197	0.5026	0.1369

Device Test: 97.3 T_RLH_LARGE(DLH Dead Time Large 500kHz VIN_14V)

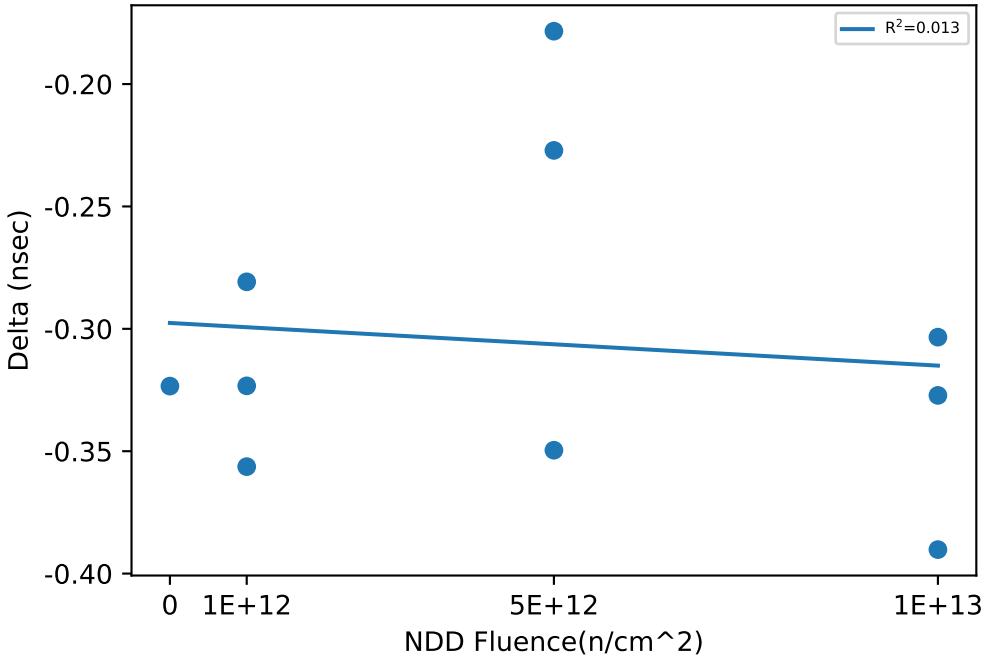
NDD vs Result Stats



Test Results (Lower Limit = 36.0, Upper Limit = 59.0 (nsec))

Serial #	Fluence(n/cm ²)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	48.206	47.925	-0.2808
551	1e+12	NDD	48.057	47.701	-0.3563
552	1e+12	NDD	49.692	49.368	-0.3233
553	5e+12	NDD	48.623	48.396	-0.2271
554	5e+12	NDD	47.851	47.502	-0.3496
555	5e+12	NDD	51.07	50.891	-0.1784
556	1e+13	NDD	48.278	47.888	-0.3902
557	1e+13	NDD	51.082	50.778	-0.3034
558	1e+13	NDD	50.601	50.274	-0.3272
559	0	NDD, Ctrl	51.538	51.214	-0.3234

NDD vs Post - Pre Exposure Delta

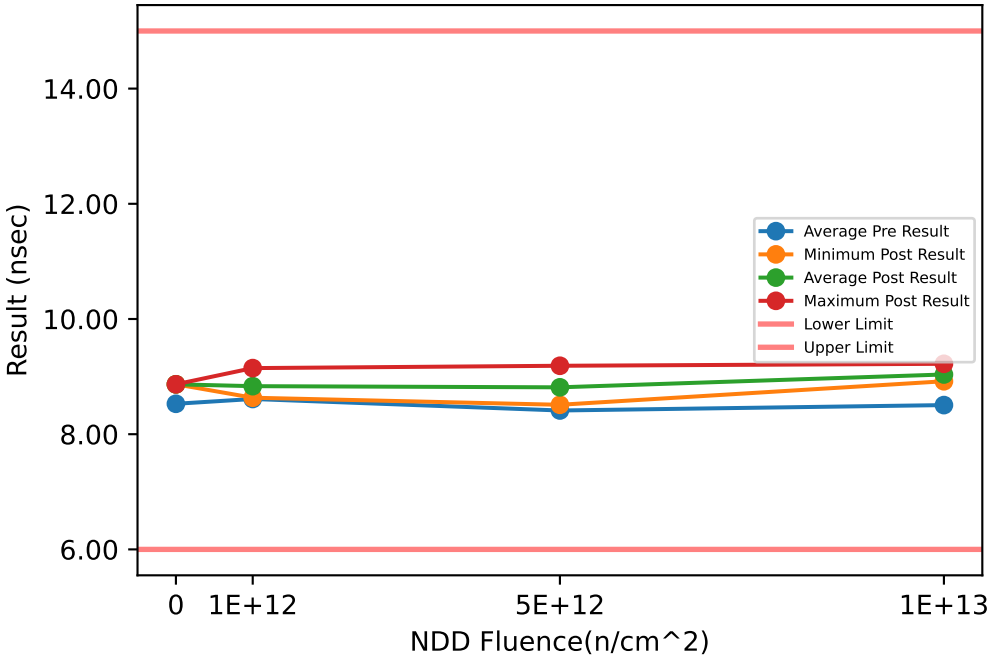


Test Statistics (nsec)

Fluence(n/cm ²)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	51.538	51.538	51.538		51.214	51.214	51.214		-0.3234	-0.3234	-0.3234	
1e+12	48.057	48.651	49.692	0.90405	47.701	48.331	49.368	0.90521	-0.3563	-0.32013	-0.2808	0.037849
5e+12	47.851	49.181	51.07	1.6803	47.502	48.93	50.891	1.7567	-0.3496	-0.2517	-0.1784	0.088211
1e+13	48.278	49.987	51.082	1.4992	47.888	49.647	50.778	1.5438	-0.3902	-0.34027	-0.3034	0.044851

Device Test: 97.30 T_RHL_SMALL(DHL Dead Time Small 2MHz VIN_14V)

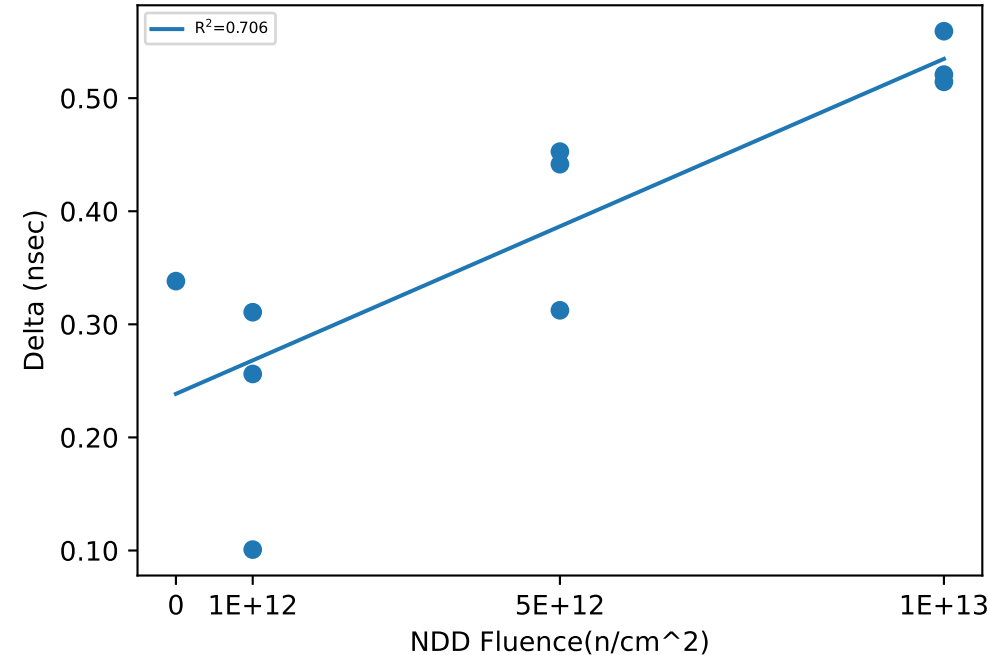
NDD vs Result Stats



Test Results (Lower Limit = 6.0, Upper Limit = 15.0 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	8.6199	8.7207	0.1008
551	1e+12	NDD	8.3773	8.6334	0.2561
552	1e+12	NDD	8.8368	9.1475	0.3107
553	5e+12	NDD	8.7464	9.188	0.4416
554	5e+12	NDD	8.2901	8.7428	0.4527
555	5e+12	NDD	8.1982	8.5106	0.3124
556	1e+13	NDD	8.4484	8.9692	0.5208
557	1e+13	NDD	8.7075	9.2219	0.5144
558	1e+13	NDD	8.3598	8.919	0.5592
559	0	NDD, Ctrl	8.528	8.8662	0.3382

NDD vs Post - Pre Exposure Delta

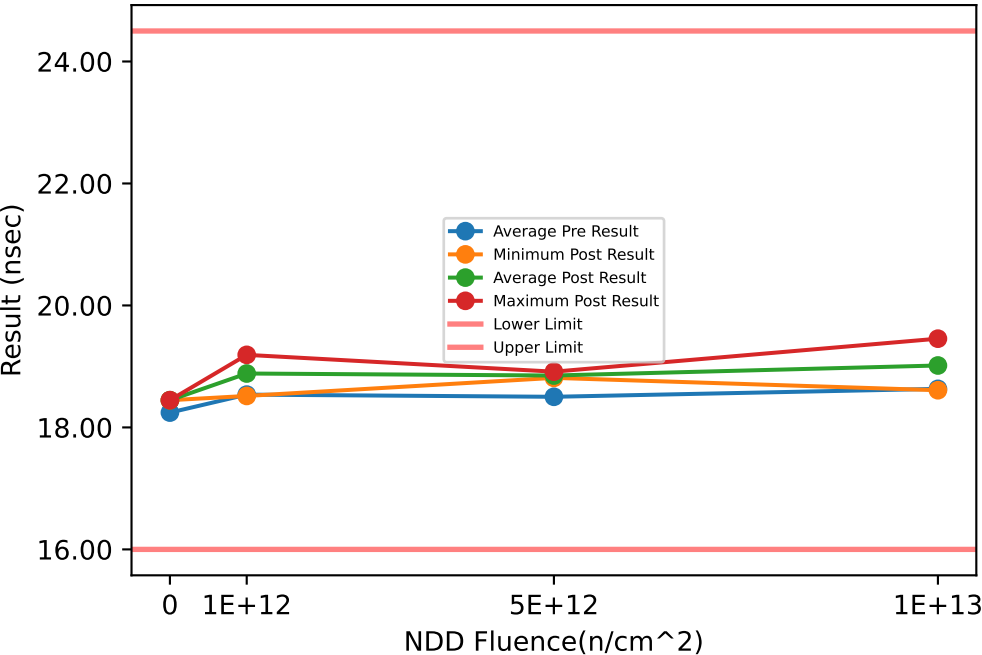


Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.528	8.528	8.528		8.8662	8.8662	8.8662		0.3382	0.3382	0.3382	
1e+12	8.3773	8.6113	8.8368	0.22987	8.6334	8.8339	9.1475	0.2751	0.1008	0.22253	0.3107	0.1089
5e+12	8.1982	8.4116	8.7464	0.29359	8.5106	8.8138	9.188	0.34424	0.3124	0.40223	0.4527	0.077996
1e+13	8.3598	8.5052	8.7075	0.18068	8.919	9.0367	9.2219	0.16234	0.5144	0.53147	0.5592	0.02423

Device Test: 97.31 T_RHL_MID(DHL Dead Time Mid 2MHz VIN_14V)

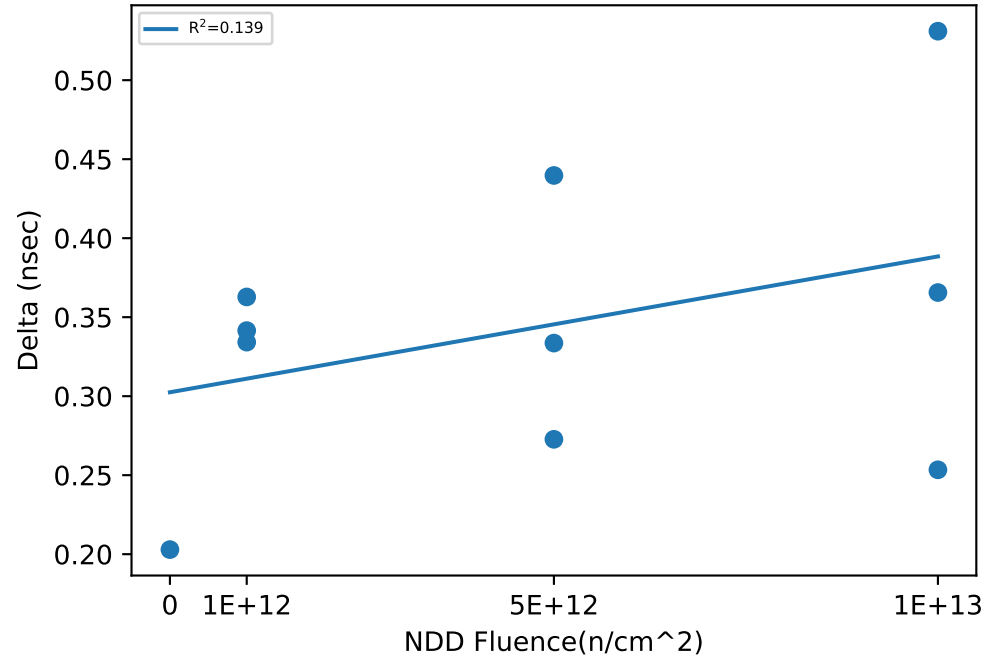
NDD vs Result Stats



Test Results (Lower Limit = 16.0, Upper Limit = 24.5 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	18.153	18.516	0.3628
551	1e+12	NDD	18.612	18.946	0.3342
552	1e+12	NDD	18.848	19.19	0.3415
553	5e+12	NDD	18.493	18.826	0.3336
554	5e+12	NDD	18.641	18.914	0.2727
555	5e+12	NDD	18.373	18.812	0.4397
556	1e+13	NDD	18.728	18.982	0.2534
557	1e+13	NDD	18.924	19.455	0.531
558	1e+13	NDD	18.244	18.61	0.3656
559	0	NDD, Ctrl	18.243	18.446	0.2029

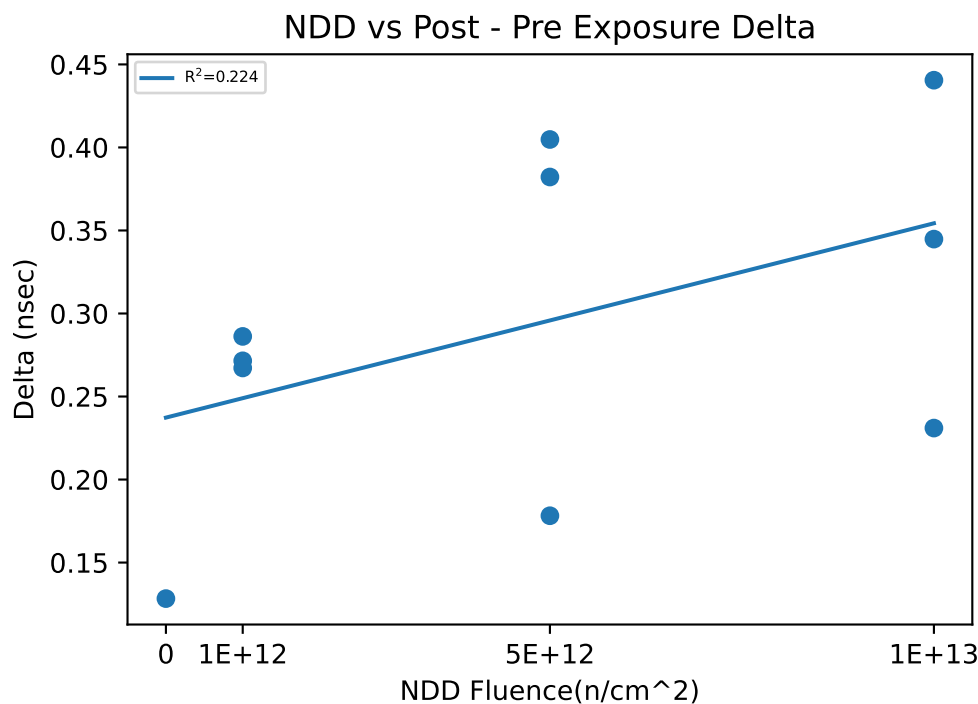
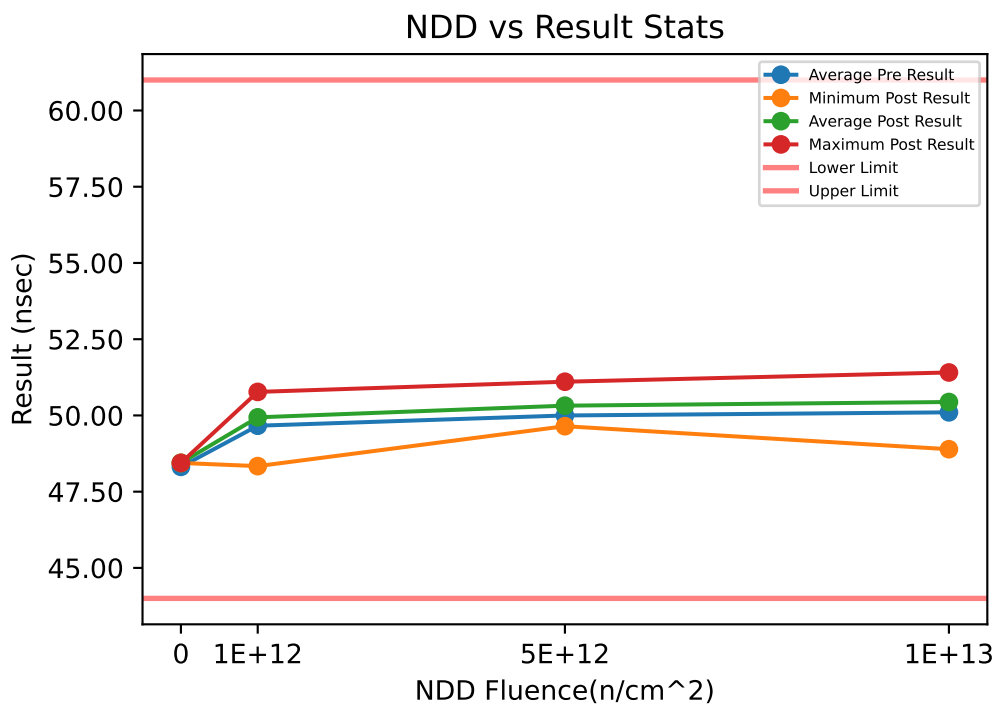
NDD vs Post - Pre Exposure Delta



Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	18.243	18.243	18.243		18.446	18.446	18.446		0.2029	0.2029	0.2029	
1e+12	18.153	18.538	18.848	0.3533	18.516	18.884	19.19	0.34104	0.3342	0.34617	0.3628	0.01486
5e+12	18.373	18.502	18.641	0.13451	18.812	18.851	18.914	0.055051	0.2727	0.34867	0.4397	0.084513
1e+13	18.244	18.632	18.924	0.34998	18.61	19.015	19.455	0.42367	0.2534	0.38333	0.531	0.13965

Device Test: 97.32 T_RHL_LARGE(DHL Dead Time Large 2MHz VIN_14V)



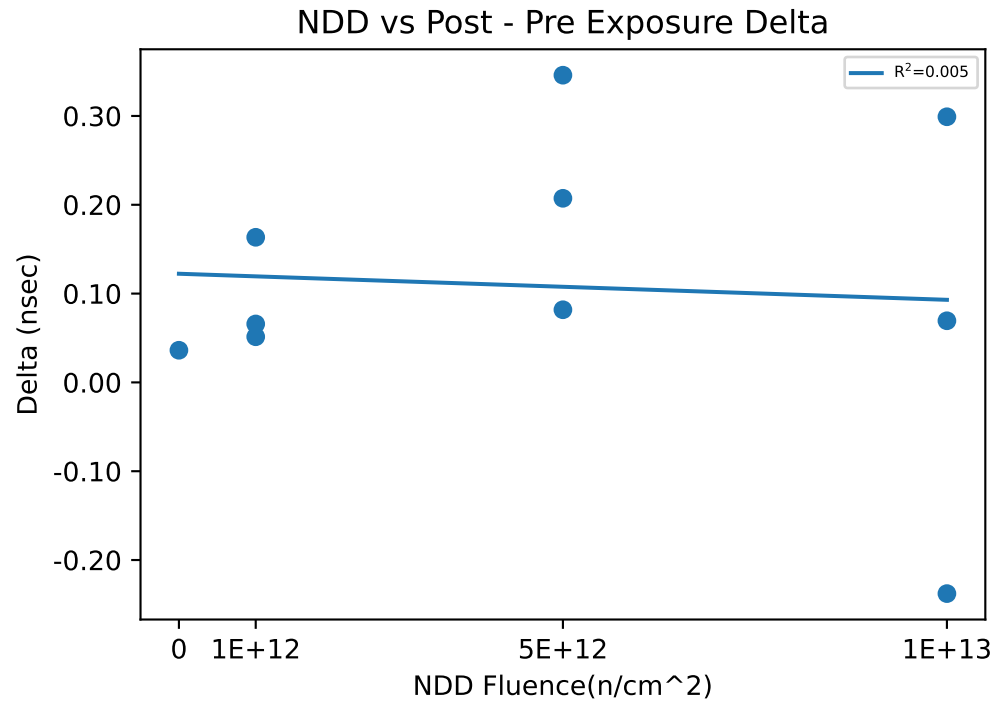
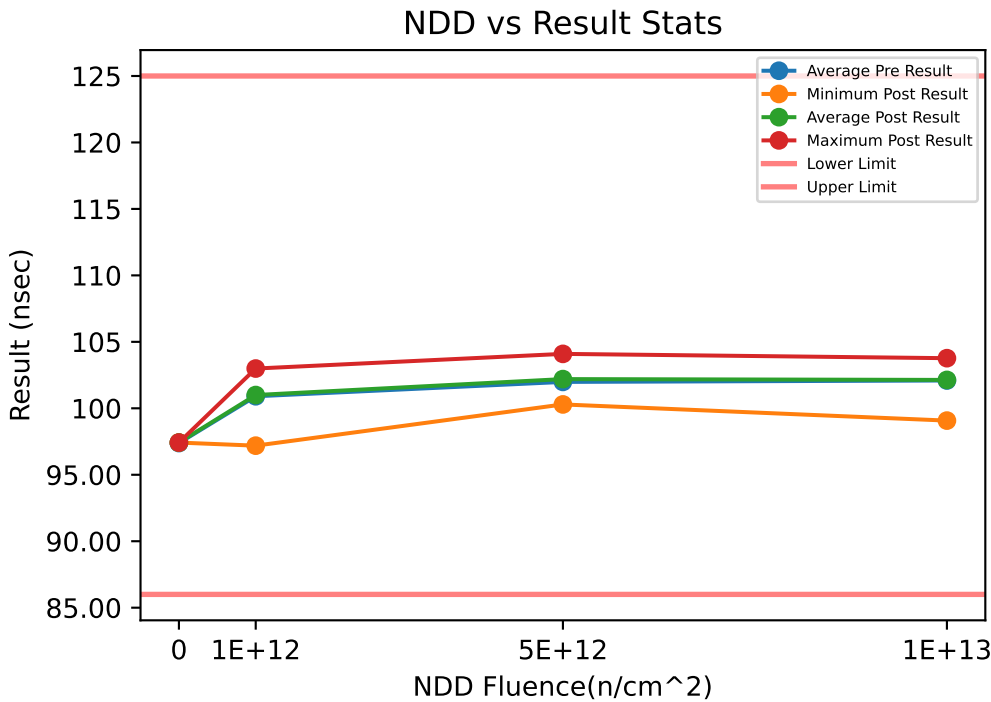
Test Results (Lower Limit = 44.0, Upper Limit = 61.0 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	48.071	48.338	0.2672
551	1e+12	NDD	50.417	50.703	0.2862
552	1e+12	NDD	50.5	50.772	0.2715
553	5e+12	NDD	49.242	49.647	0.4048
554	5e+12	NDD	50.723	51.105	0.3822
555	5e+12	NDD	50.031	50.209	0.1782
556	1e+13	NDD	50.788	51.019	0.231
557	1e+13	NDD	50.968	51.409	0.4405
558	1e+13	NDD	48.548	48.893	0.3448
559	0	NDD, Ctrl	48.314	48.442	0.1283

Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	48.314	48.314	48.314		48.442	48.442	48.442		0.1283	0.1283	0.1283	
1e+12	48.071	49.662	50.5	1.3793	48.338	49.937	50.772	1.3858	0.2672	0.27497	0.2862	0.0099631
5e+12	49.242	49.999	50.723	0.74103	49.647	50.321	51.105	0.73553	0.1782	0.32173	0.4048	0.12482
1e+13	48.548	50.101	50.968	1.3485	48.893	50.44	51.409	1.3543	0.231	0.33877	0.4405	0.10488

Device Test: 97.33 T_RHL_MAX(DHL Dead Time Max 2MHz VIN_14V)



Test Results (Lower Limit = 86.0, Upper Limit = 125.0 (nsec))

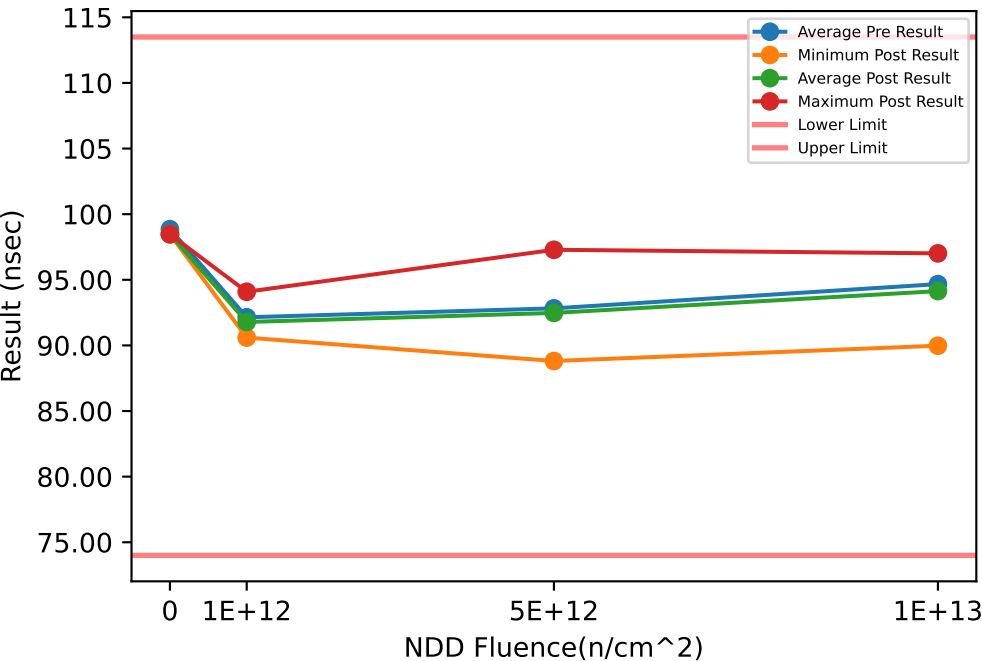
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	97.026	97.19	0.1634
551	1e+12	NDD	102.75	102.81	0.0658
552	1e+12	NDD	102.94	102.99	0.0514
553	5e+12	NDD	100.21	100.29	0.0818
554	5e+12	NDD	103.89	104.09	0.2073
555	5e+12	NDD	101.86	102.21	0.3459
556	1e+13	NDD	103.8	103.56	-0.2378
557	1e+13	NDD	103.7	103.77	0.0694
558	1e+13	NDD	98.776	99.075	0.2991
559	0	NDD, Ctrl	97.386	97.422	0.0362

Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	97.386	97.386	97.386		97.422	97.422	97.422		0.0362	0.0362	0.0362	
1e+12	97.026	100.9	102.94	3.3601	97.19	101	102.99	3.2995	0.0514	0.093533	0.1634	0.060933
5e+12	100.21	101.99	103.89	1.8418	100.29	102.2	104.09	1.9014	0.0818	0.21167	0.3459	0.1321
1e+13	98.776	102.09	103.8	2.8721	99.075	102.14	103.77	2.6525	-0.2378	0.043567	0.2991	0.26938

Device Test: 97.4 T_RLH_MAX(DLH Dead Time Max 500kHz VIN_14V)

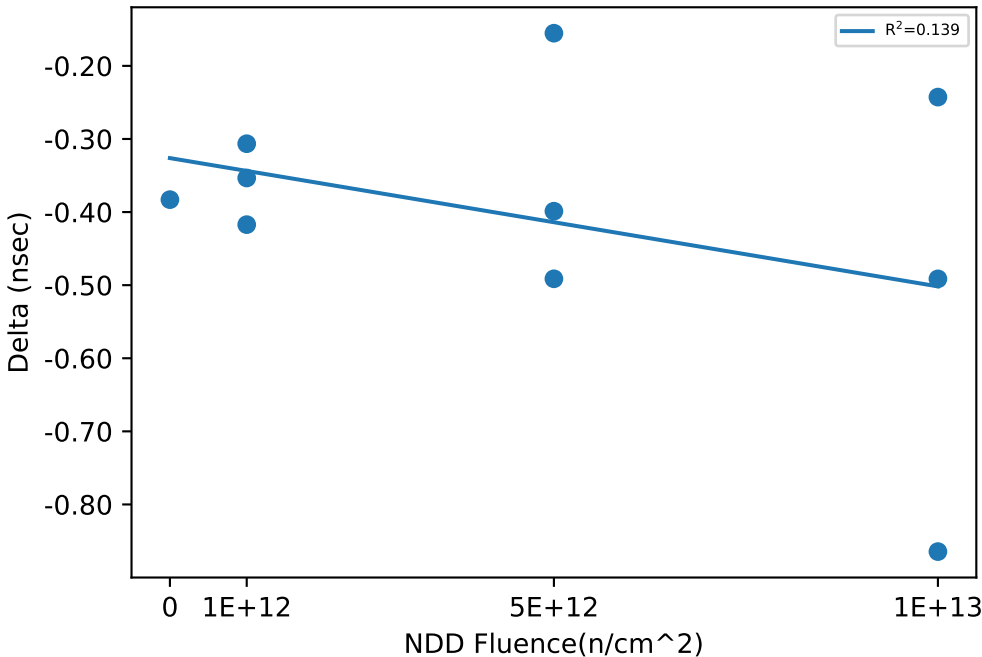
NDD vs Result Stats



Test Results (Lower Limit = 74.0, Upper Limit = 113.5 (nsec))

Serial #	Fluence(n/cm ²)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	91.023	90.67	-0.3534
551	1e+12	NDD	91.013	90.596	-0.4172
552	1e+12	NDD	94.395	94.088	-0.3065
553	5e+12	NDD	91.481	91.326	-0.1553
554	5e+12	NDD	89.304	88.813	-0.4913
555	5e+12	NDD	97.684	97.285	-0.3988
556	1e+13	NDD	90.22	89.977	-0.2427
557	1e+13	NDD	97.507	97.015	-0.4914
558	1e+13	NDD	96.284	95.42	-0.8645
559	0	NDD, Ctrl	98.857	98.474	-0.383

NDD vs Post - Pre Exposure Delta

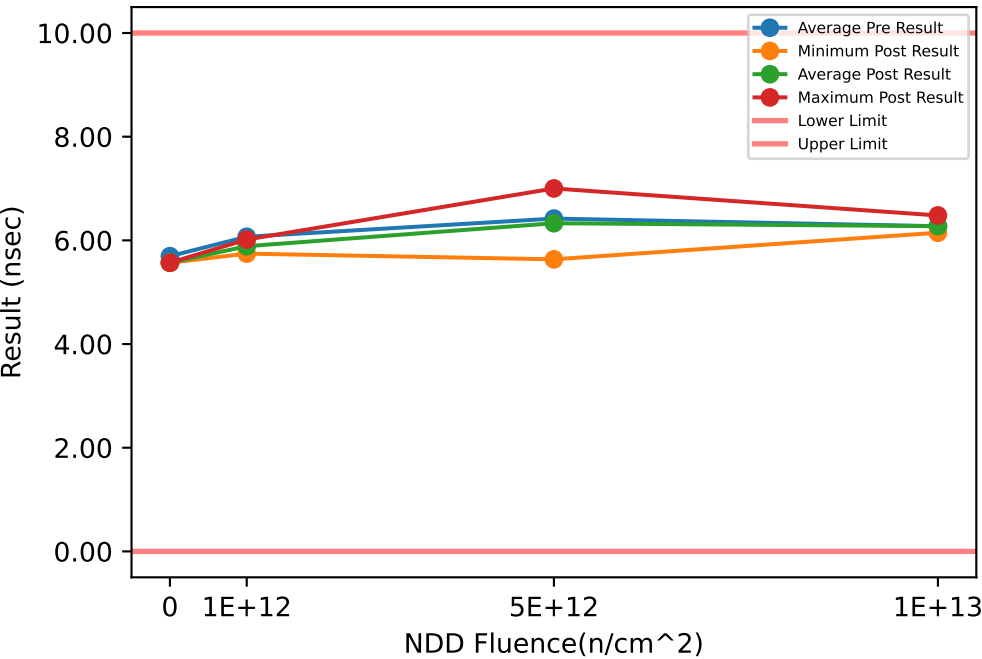


Test Statistics (nsec)

Fluence(n/cm ²)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	98.857	98.857	98.857		98.474	98.474	98.474		-0.383	-0.383	-0.383	
1e+12	91.013	92.144	94.395	1.9495	90.596	91.785	94.088	1.9953	-0.4172	-0.35903	-0.3065	0.055565
5e+12	89.304	92.823	97.684	4.3482	88.813	92.475	97.285	4.3515	-0.4913	-0.34847	-0.1553	0.17356
1e+13	90.22	94.67	97.507	3.9024	89.977	94.137	97.015	3.6902	-0.8645	-0.53287	-0.2427	0.31297

Device Test: 97.5 T_RLH_MIN(DLH Dead Time Min 1MHz VIN_14V)

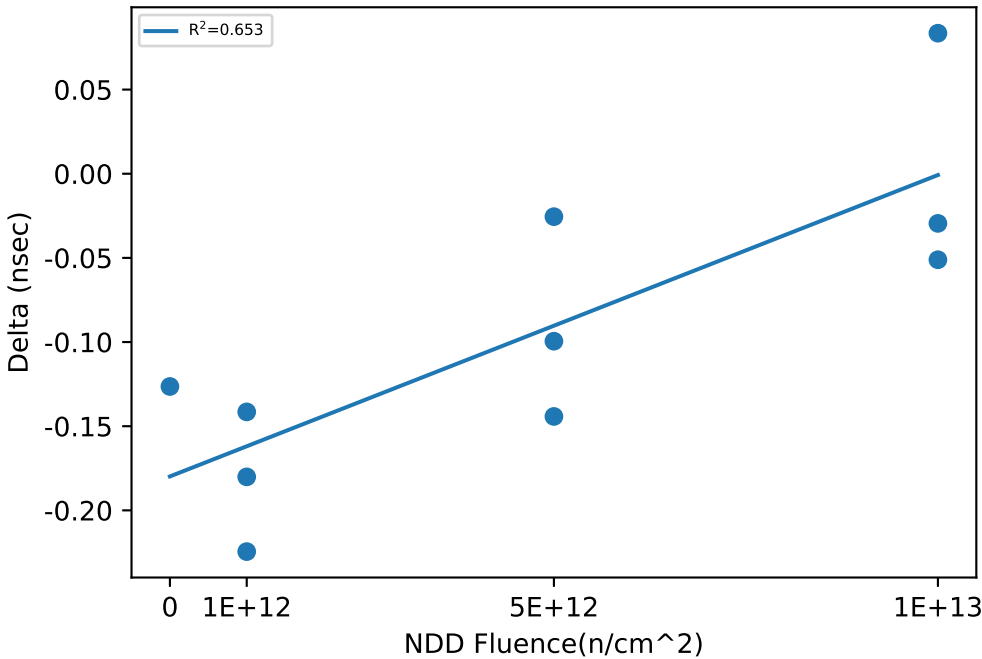
NDD vs Result Stats



Test Results (Lower Limit = 0.0, Upper Limit = 10.0 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	6.2402	6.0157	-0.2245
551	1e+12	NDD	6.0436	5.9021	-0.1415
552	1e+12	NDD	5.9241	5.744	-0.1801
553	5e+12	NDD	6.4552	6.3557	-0.0995
554	5e+12	NDD	7.1455	7.0013	-0.1442
555	5e+12	NDD	5.6595	5.634	-0.0255
556	1e+13	NDD	6.5319	6.4808	-0.0511
557	1e+13	NDD	6.11	6.1935	0.0835
558	1e+13	NDD	6.1767	6.1472	-0.0295
559	0	NDD, Ctrl	5.6947	5.5683	-0.1264

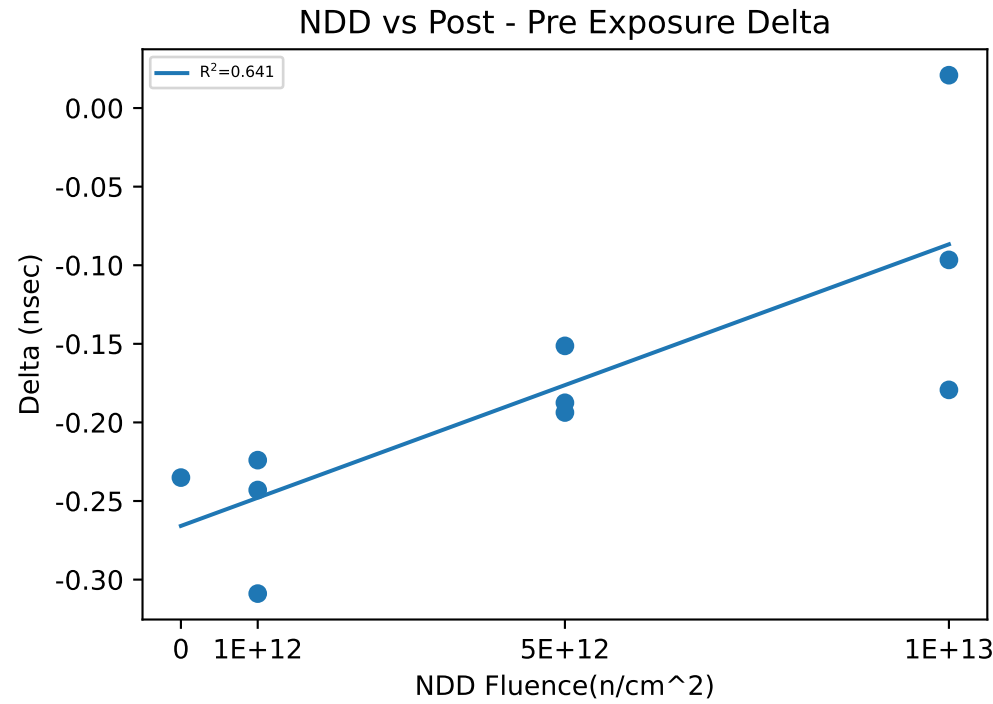
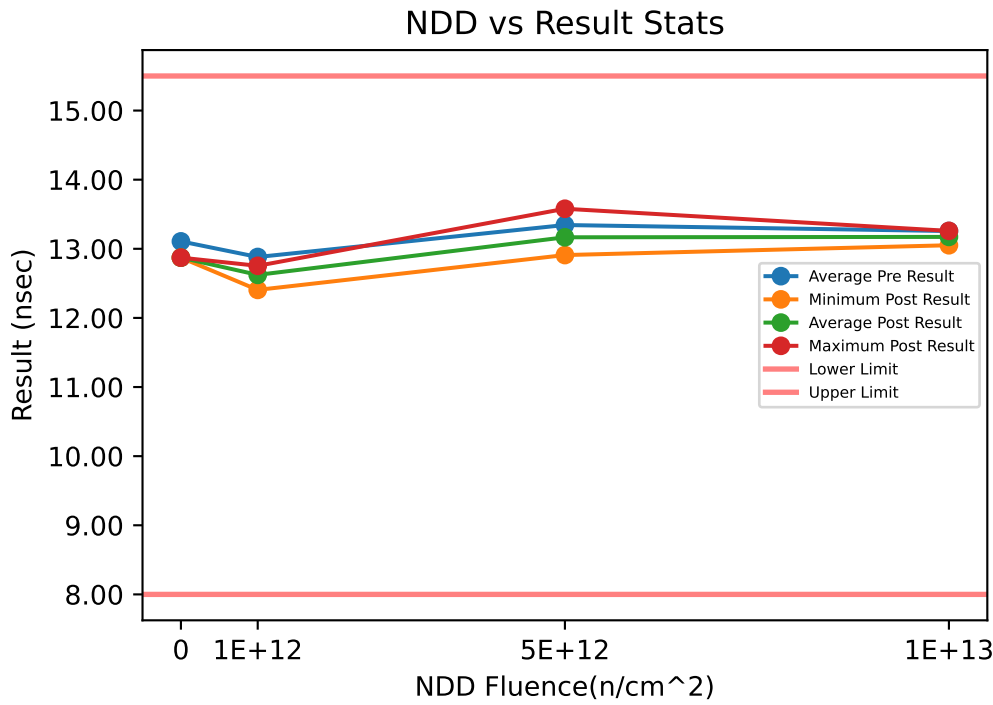
NDD vs Post - Pre Exposure Delta



Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.6947	5.6947	5.6947		5.5683	5.5683	5.5683		-0.1264	-0.1264	-0.1264	
1e+12	5.9241	6.0693	6.2402	0.15961	5.744	5.8873	6.0157	0.13646	-0.2245	-0.18203	-0.1415	0.041534
5e+12	5.6595	6.4201	7.1455	0.74362	5.634	6.3303	7.0013	0.684	-0.1442	-0.089733	-0.0255	0.05995
1e+13	6.11	6.2729	6.5319	0.22679	6.1472	6.2738	6.4808	0.18073	-0.0511	0.00096667	0.0835	0.072287

Device Test: 97.6 T_RLH_SMALL(DLH Dead Time Small 1MHz VIN_14V)



Test Results (Lower Limit = 8.0, Upper Limit = 15.5 (nsec))

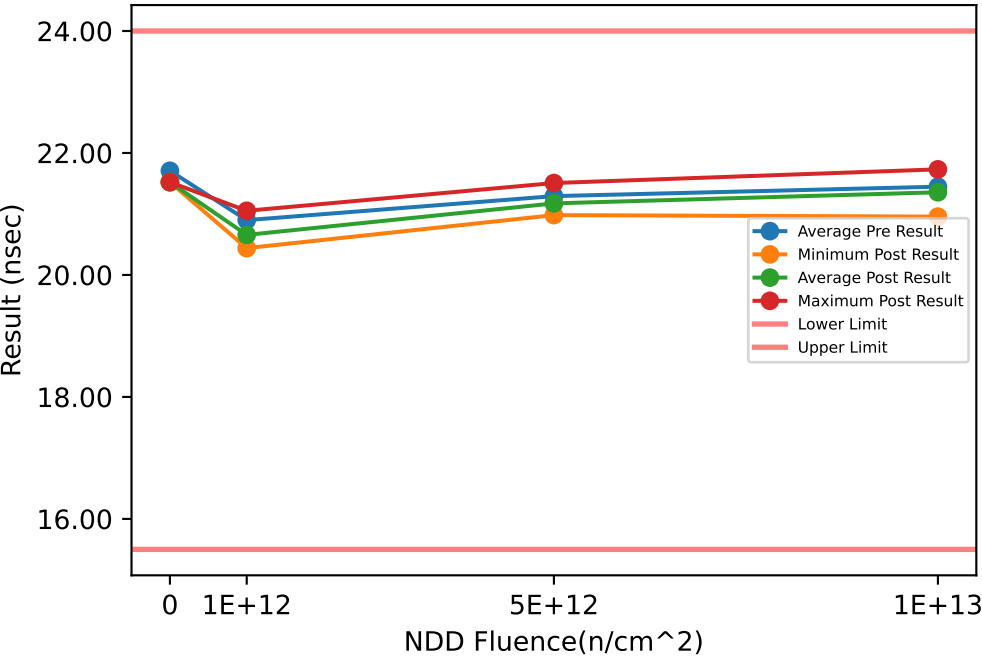
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	12.978	12.754	-0.224
551	1e+12	NDD	12.714	12.405	-0.3089
552	1e+12	NDD	12.952	12.709	-0.243
553	5e+12	NDD	13.162	13.011	-0.1513
554	5e+12	NDD	13.773	13.579	-0.1937
555	5e+12	NDD	13.097	12.909	-0.1875
556	1e+13	NDD	13.148	13.051	-0.0966
557	1e+13	NDD	13.385	13.206	-0.1793
558	1e+13	NDD	13.238	13.259	0.0209
559	0	NDD, Ctrl	13.107	12.872	-0.2351

Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	13.107	13.107	13.107		12.872	12.872	12.872		-0.2351	-0.2351	-0.2351	
1e+12	12.714	12.881	12.978	0.1453	12.405	12.623	12.754	0.18958	-0.3089	-0.25863	-0.224	0.044557
5e+12	13.097	13.344	13.773	0.37298	12.909	13.166	13.579	0.36109	-0.1937	-0.1775	-0.1513	0.022901
1e+13	13.148	13.257	13.385	0.11951	13.051	13.172	13.259	0.10787	-0.1793	-0.085	0.0209	0.1006

Device Test: 97.7 T_RLH_MID(DLH Dead Time Mid 1MHz VIN_14V)

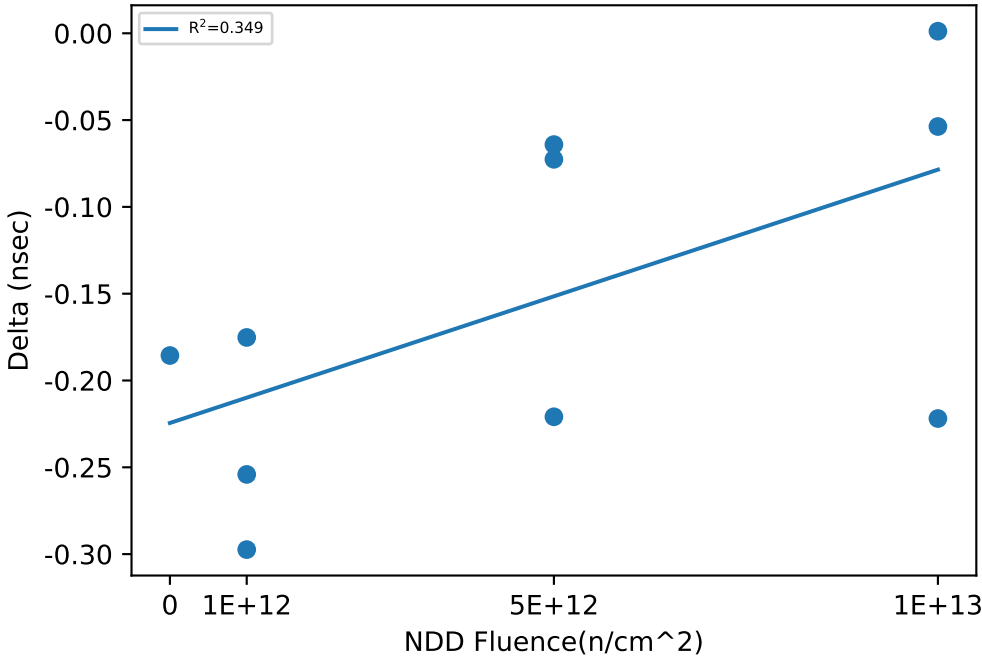
NDD vs Result Stats



Test Results (Lower Limit = 15.5, Upper Limit = 24.0 (nsec))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	20.776	20.478	-0.2974
551	1e+12	NDD	20.694	20.44	-0.2541
552	1e+12	NDD	21.227	21.052	-0.1752
553	5e+12	NDD	21.054	20.981	-0.0726
554	5e+12	NDD	21.253	21.032	-0.2209
555	5e+12	NDD	21.571	21.507	-0.0641
556	1e+13	NDD	20.955	20.956	0.0012
557	1e+13	NDD	21.785	21.731	-0.0537
558	1e+13	NDD	21.601	21.379	-0.2219
559	0	NDD, Ctrl	21.708	21.522	-0.1856

NDD vs Post - Pre Exposure Delta

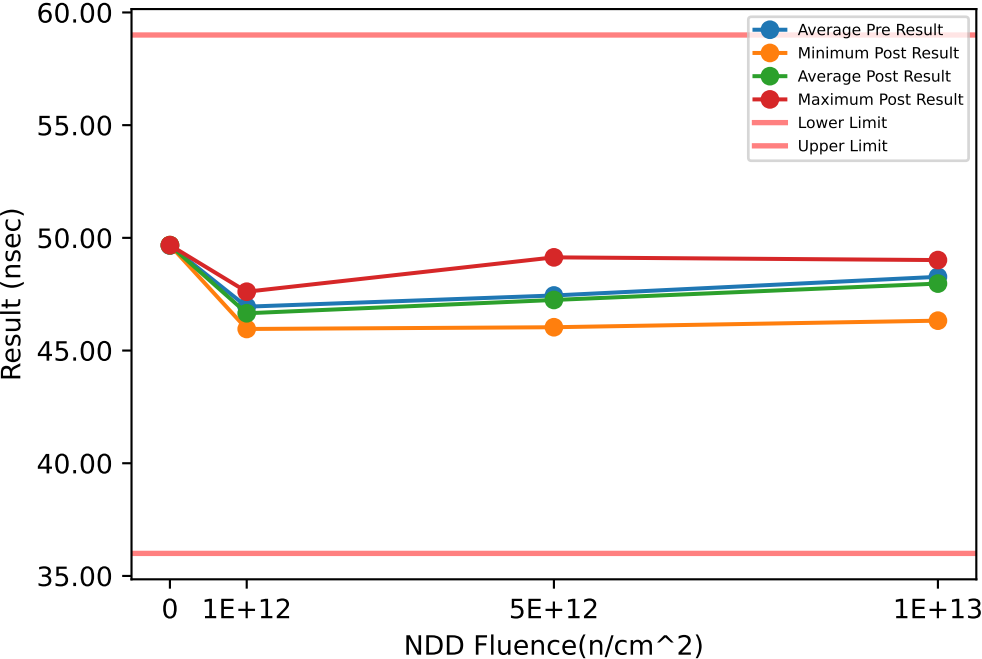


Test Statistics (nsec)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	21.708	21.708	21.708		21.522	21.522	21.522		-0.1856	-0.1856	-0.1856	
1e+12	20.694	20.899	21.227	0.28717	20.44	20.657	21.052	0.34283	-0.2974	-0.24223	-0.1752	0.061958
5e+12	21.054	21.293	21.571	0.26102	20.981	21.173	21.507	0.29009	-0.2209	-0.1192	-0.0641	0.088177
1e+13	20.955	21.447	21.785	0.4359	20.956	21.356	21.731	0.38804	-0.2219	-0.091467	0.0012	0.11625

Device Test: 97.8 T_RLH_LARGE(DLH Dead Time Large 1MHz VIN_14V)

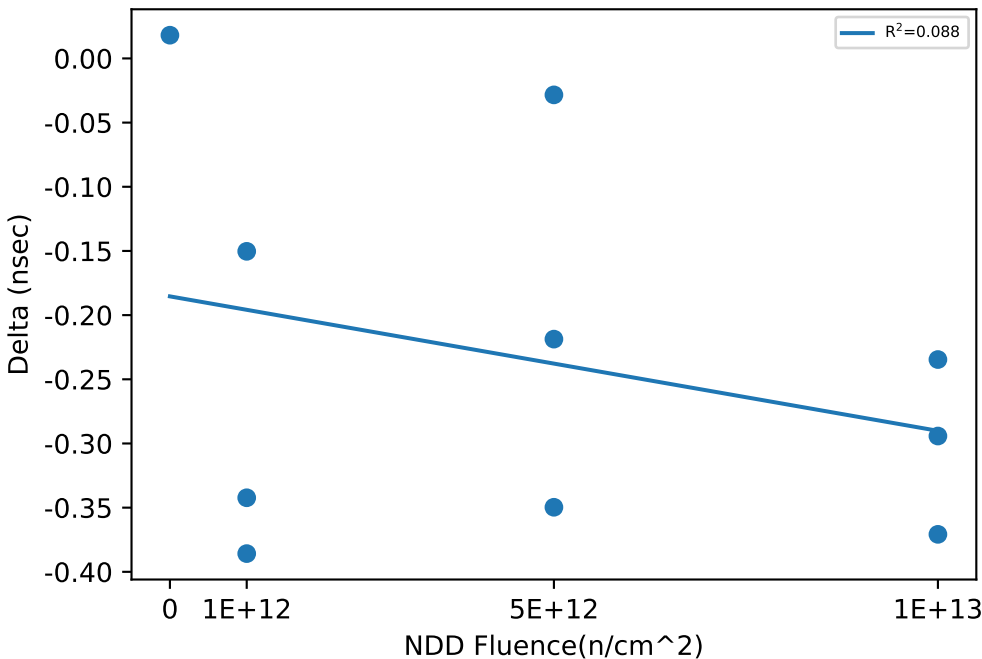
NDD vs Result Stats



Test Results (Lower Limit = 36.0, Upper Limit = 59.0 (nsec))

Serial #	Fluence(n/cm ²)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	46.544	46.393	-0.1503
551	1e+12	NDD	46.343	45.957	-0.3858
552	1e+12	NDD	47.953	47.61	-0.3423
553	5e+12	NDD	46.914	46.564	-0.3497
554	5e+12	NDD	46.253	46.034	-0.2187
555	5e+12	NDD	49.163	49.135	-0.0284
556	1e+13	NDD	46.62	46.326	-0.2942
557	1e+13	NDD	49.385	49.014	-0.3708
558	1e+13	NDD	48.807	48.572	-0.2346
559	0	NDD, Ctrl	49.658	49.676	0.0181

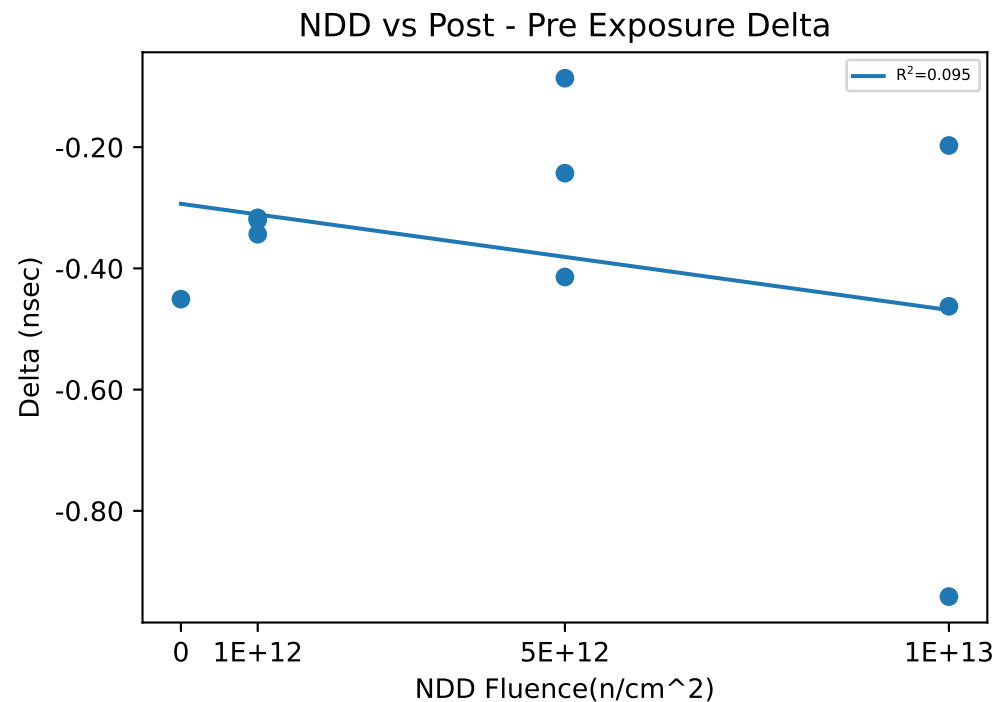
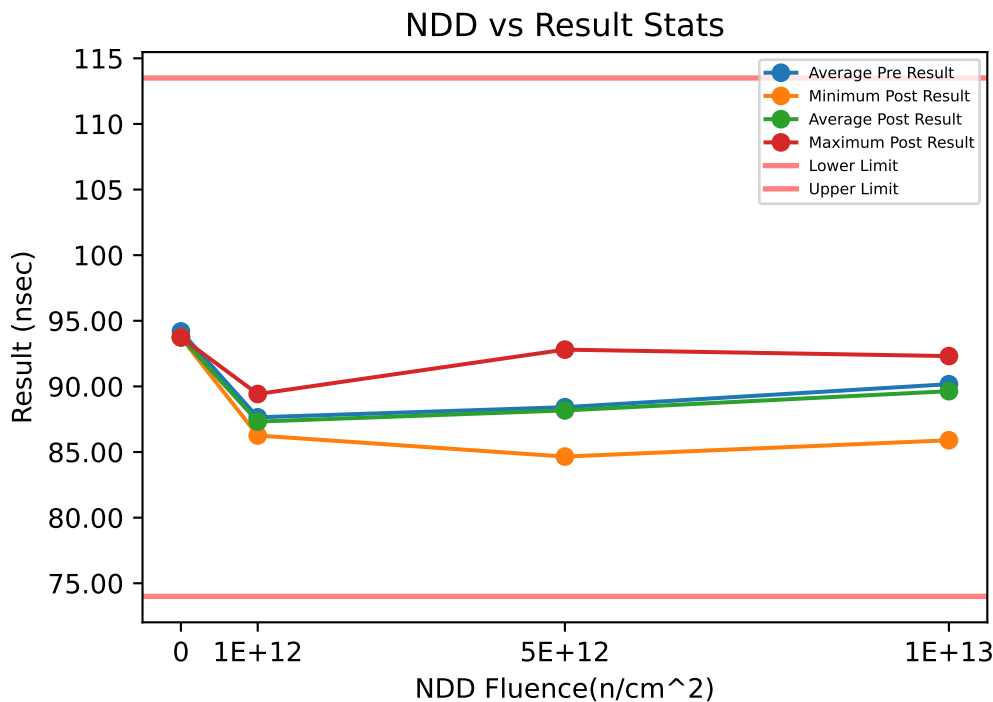
NDD vs Post - Pre Exposure Delta



Test Statistics (nsec)

Fluence(n/cm ²)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	49.658	49.658	49.658		49.676	49.676	49.676		0.0181	0.0181	0.0181	
1e+12	46.343	46.946	47.953	0.87715	45.957	46.654	47.61	0.85674	-0.3858	-0.2928	-0.1503	0.12531
5e+12	46.253	47.443	49.163	1.5257	46.034	47.244	49.135	1.6584	-0.3497	-0.19893	-0.0284	0.16156
1e+13	46.62	48.271	49.385	1.4585	46.326	47.971	49.014	1.4417	-0.3708	-0.29987	-0.2346	0.068277

Device Test: 97.9 T_RLH_MAX(DLH Dead Time Max 1MHz VIN_14V)



Test Results (Lower Limit = 74.0, Upper Limit = 113.5 (nsec))

Serial #	Fluence(n/cm ²)	Exposure Conditions	Pre Result	Post Result	Delta
550	1e+12	NDD	86.596	86.276	-0.3202
551	1e+12	NDD	86.575	86.259	-0.3166
552	1e+12	NDD	89.764	89.421	-0.3436
553	5e+12	NDD	87.139	87.053	-0.0862
554	5e+12	NDD	85.069	84.654	-0.4142
555	5e+12	NDD	93.046	92.803	-0.2429
556	1e+13	NDD	86.093	85.896	-0.1972
557	1e+13	NDD	92.773	92.311	-0.4626
558	1e+13	NDD	91.642	90.7	-0.9415
559	0	NDD, Ctrl	94.191	93.74	-0.4507

Test Statistics (nsec)

Fluence(n/cm ²)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	94.191	94.191	94.191		93.74	93.74	93.74		-0.4507	-0.4507	-0.4507	
1e+12	86.575	87.645	89.764	1.8353	86.259	87.318	89.421	1.8207	-0.3436	-0.3268	-0.3166	0.01466
5e+12	85.069	88.418	93.046	4.1395	84.654	88.17	92.803	4.1876	-0.4142	-0.24777	-0.0862	0.16405
1e+13	86.093	90.169	92.773	3.5752	85.896	89.636	92.311	3.3373	-0.9415	-0.53377	-0.1972	0.37722

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